

Radiation Report

TPS7H5020-SEP Total Ionizing Dose (TID) Preliminary Report



ABSTRACT

This report discusses the results of the total ionizing dose (TID) testing for the Texas Instruments TPS7H5020-SEP radiation hardness-assured 1.2A, PWM controller with integrated gate driver. The study was done to determine TID effects at 50krad (Si) High Dose Rate (HDR). The results show that all samples pass within device specified test limits.

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1 Device Information

1.1 Product Description

The TPS7H5020 is a radiation-hardness-assured, current mode, single-ended PWM controller with an integrated gate driver that can be utilized in both silicon and gallium nitride (GaN) power semiconductor based converter designs. The TPS7H502x integrates several key functions, such as soft-start, enable, and adjustable slope compensation while maintaining a small package size. The controller also features a $0.6V \pm 1\%$ voltage reference tolerance to support highly accurate power converter designs. The TPS7H5020-SEP is packaged in a plastic 24-pin HTSSOP PWP package.

1.2 Device Details

Testing was performed per MIL-STD-883, Test Method 1019, with a sample size per MIL-PRF-38535, Appendix C, test condition A (high dose rate).

Table 1-1. Device and Exposure Details

RHA TID Details: Up to 100krad(Si)	
TI Part Number	TPS7H5020-SEP
Device Function	PWM Controller with Integrated Gate Driver
Package	24-pin HTSSOP-PWP
Technology	LBC7 (250nm Linear BiCMOS)
Quantity tested	HDR : • Five biased and five unbiased units at 50krad(Si) levels • One correlation unit
Lot Accept/Reject	Passes 50krad(Si); no observed fails
HDR Radiation Facility	Texas Instruments CLAB Dallas, Texas
Die Lot Number and Assembly Lot Number	DIE: 4087898 Assembly: 4628068
HDR Dose Rate	172.96 rad (Si) / s
HDR Radiation Source	Gammacell 220 Excel (GC-220E) Co-60
Irradiation and Test Temperature	Ambient, room temperature controlled to $25^{\circ}C \pm 6^{\circ}C$ per MIL-STD-883 and MIL-STD-750



Figure 1-1. Device Used in Exposure (Front)

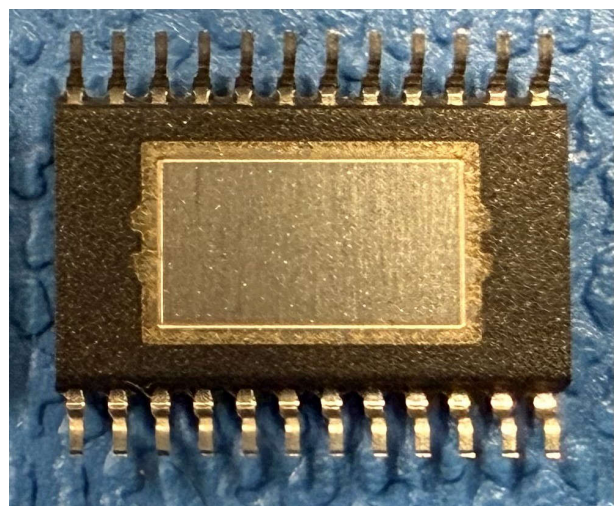


Figure 1-2. Device Used in Exposure (Back)

2 Total Dose Test Setup

2.1 Test Overview

The TPS7H5020-SEP was tested according to MIL-STD-883, Test Method 1019.9. For this testing, condition A was used. For this test, the product was irradiated up to the target radiation level, and then put through full electrical parametric testing on the production Automated Test Equipment (ATE). All devices remained functional passing all parametric test limits.

2.2 Test Description and Facilities

The TPS7H5020-SEP HDR exposure was performed on biased devices in a Co-60 Gammacell at the TI Dallas C-Lab facility in Dallas, Texas. The unattenuated dose rate of this cell is 172.96 rad (Si) / s. After exposure, the devices were packed in dry ice (per MIL-STD-883 Method 1019.9 section 3.10) and post-radiation electrical testing at TI's Dallas Forest Lane facility. Test limit guard bands are set within SMD electrical test limits.

Post-radiation measurements were taken within 30 minutes after removing device from the dry ice container. The devices were allowed to reach room temperature prior to electrical post-radiation measurements.

2.3 Test Setup Details

The devices under HDR exposure were tested in two conditions, biased and unbiased, as described in the following sections.

2.3.1 Unbiased

For the unbiased HDR conditions, the exposure was performed with all pins grounded.

2.3.2 Biased

Figure 2-1 through Figure 2-3 and the HDR bias diagram and schematic.

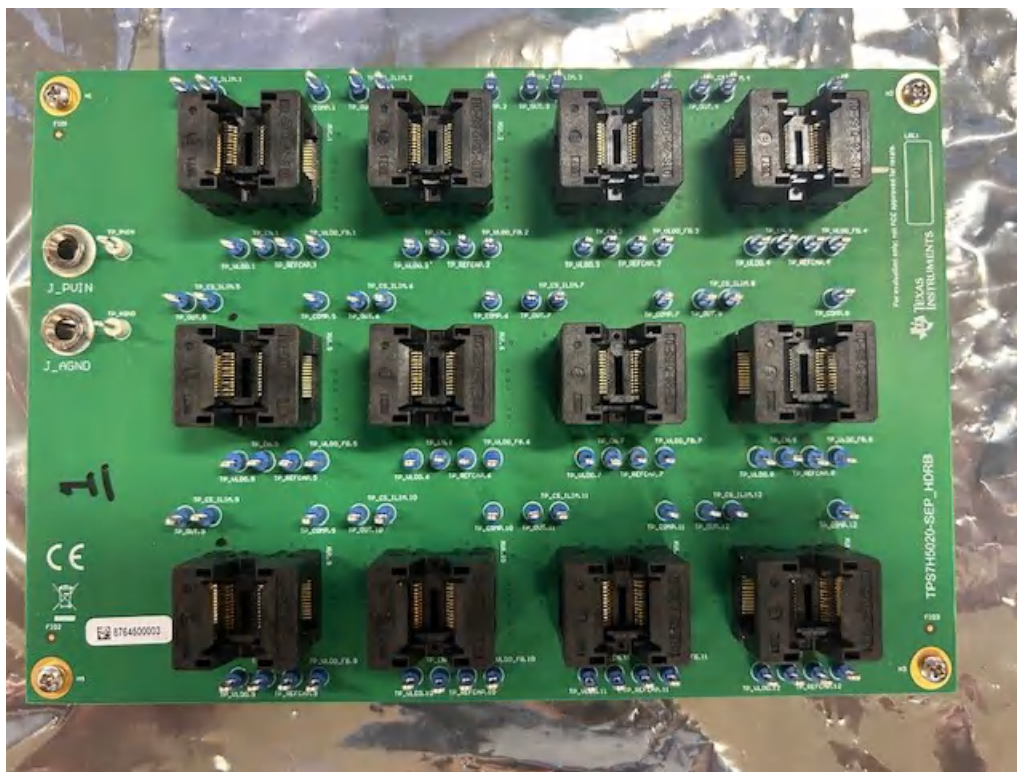


Figure 2-1. HDR TID Hardware

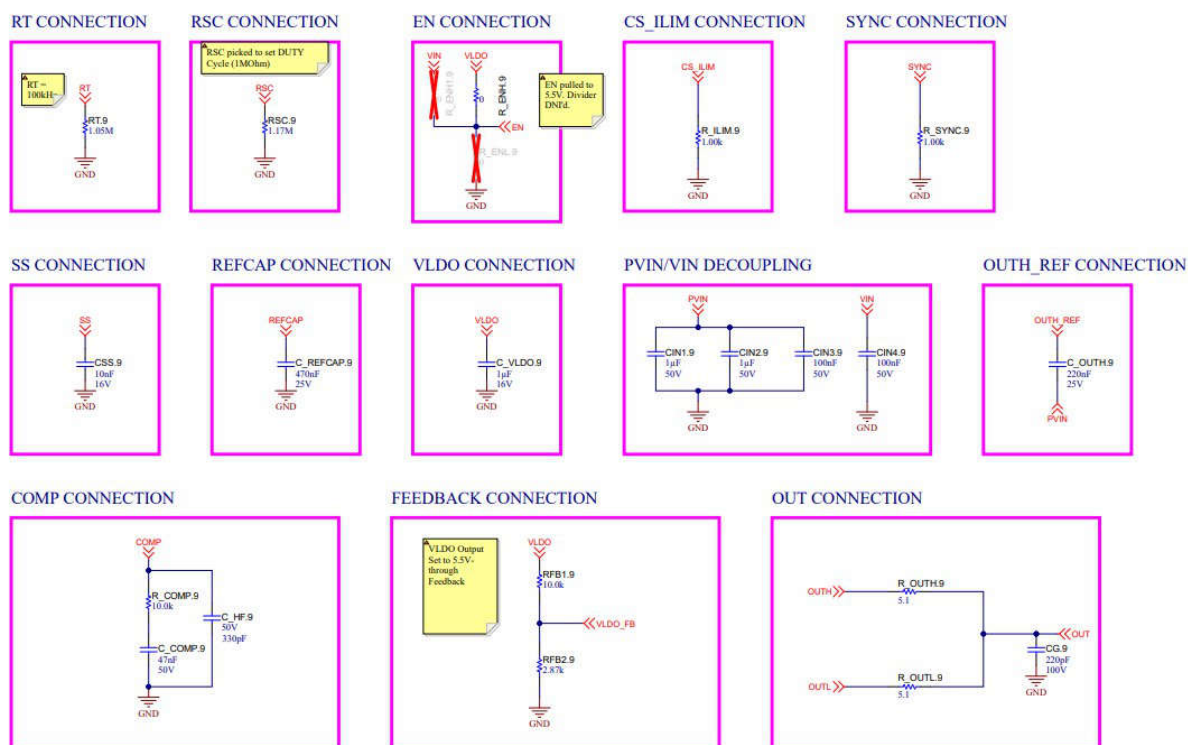


Figure 2-2. Supplies and GND HDR TID Bias Diagram

SITE - SOCKET PIN MAPPING

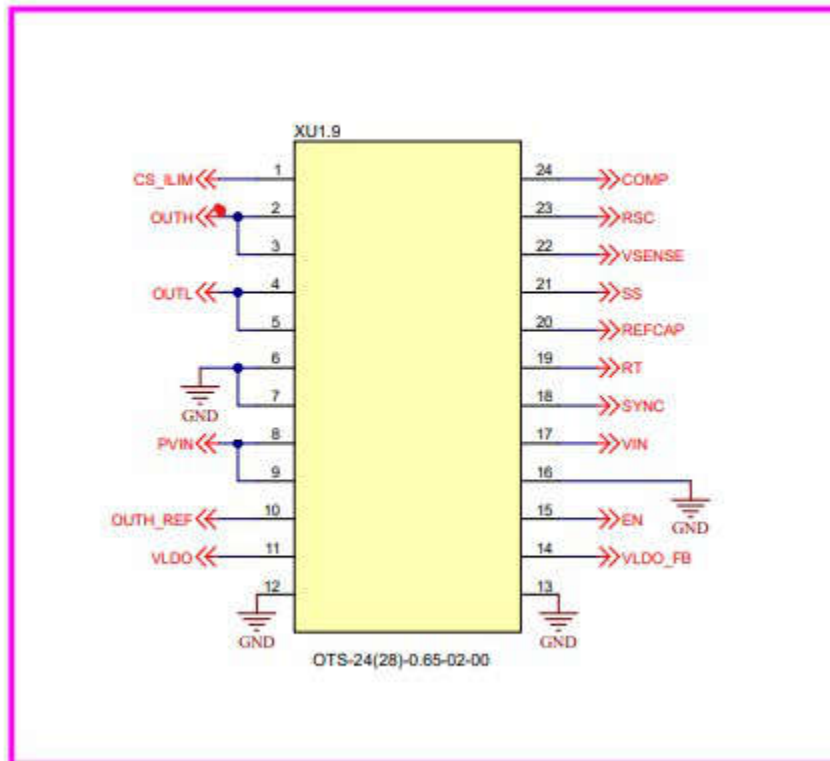


Figure 2-3. HDR TID Bias Diagram

2.4 Test Configuration and Conditions

HDR devices were stressed up to 50krad (Si) for biased and unbiased conditions.

Table 2-1. HDR Biased Device Information

Total Samples: 5 units + 2 control	
Exposure Levels:	
Control	50krad (Si)
1, 2	4, 6, 7, 8, 9

Table 2-2. HDR Unbiased Device Information

Total Samples: 5 units + 2 control	
Exposure Levels:	
Control	50krad (Si)
1, 2	11, 12, 13, 14, 15

3 TID Characterization Test Results

3.1 TID Characterization Results Summary

The results show that all TPS7H5020-SEP devices were fully functional and within specification limits up to 50krad (Si) HDR. Overall the TPS7H5020-SEP show a strong degree of hardness to TID HDR exposure levels at 50krad (Si) under bias and unbiased conditions. Performance is measured based on the difference between pre- and post-irradiation with respect to SMD electrical minimum and maximum specification. The measurements taken post-irradiation for each sample set showed a marginal shift for most parameters at each dose level for both biased and unbiased. (see [Section 3.2](#) for the electrical parameters). Note that test numbers are listed only for parameters tested post-TID.

See [Appendix: HDR TID Report](#) for HDR report.

3.2 Data Sheet Electrical Parameters

Specifications are at ambient temperature $T_A = 25^\circ\text{C}$, $P_{VIN}=V_{IN}= 4.5\text{V}$ to 14V unless otherwise noted.

Table 3-1. TPS7H5020-SEP Data Sheet Electrical Parameters

Parameters		Test Conditions		Min	Max	Units	Test Number
SUPPLY VOLTAGES AND CURRENTS							
IDD	Operating supply current	No load for OUT, PVIN = VIN	f _{SW} = 100kHz	10		mA	14.1, 14.2, 14.3, 14.5
			f _{SW} = 500kHz	15.5		mA	14.6, 14.8, 14.10, 14.12,
			f _{SW} = 1MHz	18		mA	14.14, 14.15, 14.16, 14.17
		C _{LOAD} = 1000pF for OUT, PVIN = VIN	f _{SW} = 100kHz	12		mA	14.18, 14.19, 14.20, 14.21
			f _{SW} = 500kHz	20		mA	14.22, 14.23, 14.24, 14.25
			f _{SW} = 1MHz	28		mA	14.26, 14.27, 14.28, 14.29
		C _{LOAD} = 1000pF for OUT, VIN = 12V, PVIN = VLDO = 5V	f _{SW} = 100kHz	10		mA	14.3
			f _{SW} = 500kHz	13		mA	14.31
			f _{SW} = 1MHz	20		mA	14.32
I _{start}	Startup current	VIN = 3.5V	VIN = 3.5V	5		mA	14.5
I _{DD(dis)}	Standby current	EN = 0V	EN = 0V	7		mA	14.7, 14.9, 14.11, 14.13,
VLDO	Internal linear regulator output voltage	C _{VLDO} = 1μF	5V ≤ VIN ≤ 14V, RVT = 10kΩ, RVB = 3.74kΩ	4.36	4.62	V	15.1, 15.4, 15.5
			5.5V ≤ VIN ≤ 14V, RVT = 10kΩ, RVB = 3.24kΩ	4.84	5.14	V	15.8, 15.11, 15.12
			6V ≤ VIN ≤ 14V, RVT = 10 kΩ, RVB = 2.87kΩ	5.31	5.65	V	15.15, 15.18, 15.19
VLDO_DO	Internal linear dropout voltage	I _{VLDO} = 25mA, C _{VLDO} = 1μF	I _{VLDO} = 25mA, C _{VLDO} = 1μF	0.4		V	15.40, 15.41, 15.42, 15.43, 15.44, 15.45
I_VLDO	VLDO output current	VLDO ≥ 96% of VLDO at no load, C _{VLDO} = 1μF	VIN = VLDO + 0.5V	30		mA	15.3, 15.10, 15.17
			VIN = VLDO + 1V	60		mA	15.34, 15.35, 15.36
			VIN ≥ 7V	95		mA	15.7, 15.14, 15.21, 15.37, 15.38, 15.39
ENABLE AND UNDERVOLTAGE LOCKOUT							
V _{ENR}	Enable rising threshold			0.57	0.66	V	16.1, 16.4, 16.7, 16.10
V _{ENF}	Enable falling threshold			0.48	0.55	V	16.2, 16.5, 16.8, 16.11

Table 3-1. TPS7H5020-SEP Data Sheet Electrical Parameters (continued)

Parameters		Test Conditions		Min	Max	Units	Test Number
I_{EN}	Enable input leakage current	$V_{IN} = 14V$	$EN = 1V$		100	nA	16.15, 16.17
			$EN = 7V$		250	nA	16.16, 16.18
$PV_{INUVLOR}$	PVIN UVLO rising			3.65	3.95	V	17.1, 17.10, 17.19
$PV_{INUVLOF}$	PVIN UVLO falling			3.45	3.75	V	17.2, 17.11, 17.20
$V_{INUVLOR}$	VIN UVLO rising			3.85	4.15	V	17.4, 17.13, 17.22
$V_{INUVLOF}$	VIN UVLO falling			3.65	3.95	V	17.5, 17.14, 17.23
$VLDO_{UVLOR}$	VLDO UVLO rising			3.65	3.95	V	17.7, 17.16, 17.25
$VLDO_{UVLOF}$	VLDO UVLO falling			3.45	3.75	V	17.8, 17.17, 17.26
SOFT START							
I_{SS}	Soft-start current	$SS = 0.3V$	$SS = 0.3V$	2	3.3	μA	18.1, 18.5, 18.9, 18.13, 18.17, 18.21, 18.25, 18.29, 18.33, 18.37, 18.41, 18.45
ERROR AMPLIFIER							
EA_{gm}	Error amplifier transconductance	$-10\mu A < I_{COMP} < 10\mu A$, $V_{(COMP)} = 1V$	$-10\mu A < I_{COMP} < 10\mu A$, $V_{(COMP)} = 1V$	1150	2650	$\mu A/V$	19.1, 19.5, 19.9, 19.13
EA_{ISRC}	Error amplifier source current	$V_{(COMP)} = 1V$, 100mV input overdrive	$V_{(COMP)} = 1V$, 100mV input overdrive	95	195	μA	19.2, 19.6, 19.10, 19.14
EA_{ISNK}	Error amplifier sink current	$V_{(COMP)} = 1V$, 100mV input overdrive	$V_{(COMP)} = 1V$, 100mV input overdrive	95	195	μA	19.3, 19.7, 19.11, 19.15
EA_{OS}	Error amplifier input offset voltage			-4.5	5.5	mV	19.27, 19.3, 19.33, 19.36, 19.39, 19.42, 19.45, 19.48, 19.51, 19.54, 19.57, 19.6
EA_{IB}	Error amplifier input bias current				25	nA	19.4, 19.8, 19.12, 19.16, 19.17, 19.18, 19.19, 19.20, 19.21, 19.22, 19.23, 19.24
OSCILLATOR							

Table 3-1. TPS7H5020-SEP Data Sheet Electrical Parameters (continued)

Parameters		Test Conditions		Min	Max	Units	Test Number
DT _{INT}	External clock to internal clock detection time	RT populated	RT populated	5		(1/f _{sw}) s	20.144, 20.146, 20.148, 20.150, 20.152, 20.154, 20.156, 20.158, 20.160, 20.162, 20.164, 20.166, 20.168, 20.170, 20.172, 20.174
DT _{EXT}	Internal clock to external clock detection time	RT populated	RT populated	5		(1/f _{sw}) s	20.112, 2.114, 2.116, 2.118, 2.120, 2.122, 2.124, 2.126, 2.128, 2.130, 2.132, 2.134, 2.136, 2.138, 2.140, 2.142
f _{sw}	RT programmed switching frequency	RT = 1.18MΩ	RT = 1.18MΩ	80	110	kHz	20.15, 20.19, 20.23, 20.27, 20.71, 20.73, 20.75, 20.77
		RT = 560kΩ	RT = 560kΩ	180	220	kHz	20.31, 20.33, 20.35, 20.37, 20.79, 20.81, 20.83, 20.85
		RT = 210kΩ	RT = 210kΩ	475	550	kHz	20.39, 20.43, 20.47, 20.51, 20.87, 20.89, 20.91, 20.93
		RT = 100kΩ	RT = 100kΩ	950	1100	kHz	20.55, 20.59, 20.63, 20.67, 20.95, 20.97, 20.99, 20.101
VOLTAGE REFERENCE							
VREF	Internal voltage reference	Measured at COMP, COMP = VSENSE	T _A = 25°C	0.597	0.603	V	19.25, 19.28, 19.31, 19.34, 19.37, 19.4, 19.43, 19.46, 19.49, 19.52, 19.55, 19.58, 19.61, 19.63, 19.65, 19.67, 19.69, 19.71, 19.73, 19.75, 19.77, 19.79, 19.81, 19.83

Table 3-1. TPS7H5020-SEP Data Sheet Electrical Parameters (continued)

Parameters		Test Conditions		Min	Max	Units	Test Number
REFCAP	REFCAP voltage	$C_{REFCAP} = 470\text{nF}$	$C_{REFCAP} = 470\text{nF}$	1.211	1.235	V	21.1, 21.3, 21.5, 21.7, 21.9, 21.11, 21.13, 21.15, 21.17, 21.19, 21.21, 21.23, 21.25, 21.27, 21.29, 21.31, 21.33, 21.35, 21.37, 21.39, 21.41, 21.43, 21.45, 21.47
CURRENT SENSE							
CCSR	COMP to CS_ILIM ratio	RSC = open	RSC = open	1.94	2.06		28.1, 28.2, 28.3, 28.4
V_{CS_ILIM}	Current limit (overcurrent) threshold			0.96	1.04	V	28.9, 28.10, 28.11, 28.12, 28.13, 28.14, 28.15, 28.16, 28.17, 28.18, 28.19, 28.20
	CS_ILIM to OUT delay	CS_ILIM = 1V to 90% of OUT falling	CS_ILIM = 1V to 90% of OUT falling		115	ns	28.21, 28.22, 28.23, 28.24, 28.25, 28.26, 28.27, 28.28, 28.29, 28.30, 28.31, 28.32, 28.33, 28.34, 28.35, 28.36, 28.37, 28.38, 28.39, 28.40, 28.41, 28.42, 28.43, 28.44
GATE DRIVER							
V_{OL}	Low-level voltage	$I_{OL} = 50\text{mA}$	$I_{OL} = 50\text{mA}$		0.15	V	24.1, 24.3, 24.5, 24.7
PVIN - V_{OH}	High-level voltage	$I_{OH} = 50\text{mA}$	$I_{OH} = 50\text{mA}$		0.25	V	24.2, 24.4, 24.6, 24.8
t_{R_OUT}	OUT rise time	$C_{LOAD} = 1000\text{pF}$, 10% to 90%	VIN = 12V, PVIN = VLDO		16	ns	24.17, 24.19, 24.21
		$C_{LOAD} = 220\text{pF}$, 10% to 90%	VIN = 12V, PVIN = VLDO		12	ns	24. 23, 24.25, 24.27
t_{F_OUT}	OUT fall time	$C_{LOAD} = 1000\text{pF}$, 90% to 10%	VIN = 12V, PVIN = VLDO		16	ns	24.18, 24.20, 24.22
		$C_{LOAD} = 220\text{pF}$, 90% to 10%	VIN = 12V, PVIN = VLDO		12	ns	24. 24, 24.26, 24.28
I_{OH}	Peak source current	PVIN = 4.5V	PVIN = 4.5V			A	23.1
		PVIN = 5V	PVIN = 5V			A	23.3

Table 3-1. TPS7H5020-SEP Data Sheet Electrical Parameters (continued)

Parameters		Test Conditions		Min	Max	Units	Test Number
I _{OL}	Peak sink current	PVIN = 4.5V	PVIN = 4.5V			A	23.2
		PVIN = 5V	PVIN = 5V			A	23.4
R _{OH}	Pull-Up Resistance	100mA from OUT	100mA from OUT		4.7	Ω	23.5, 23.7, 23.9, 23.11
R _{OL}	Pull-Down Resistance	100mA into OUT	100mA into OUT		2.8	Ω	23.6, 23.8, 23.10, 23.12
V _{UCLAMP}	Unpowered OUT clamp voltage	Switching disabled, SYS_ON = 0, 1mA pull-up applied to OUT	PVIN = 0V		1	V	24.29
			0V < PVIN < 5V		2.5	V	24.3
PWM AND DUTY CYCLE							
T _{LEB}	Leading edge blank time	5V ≤ VIN ≤ 14V, 10% of OUT rising to end of blanking	5V ≤ VIN ≤ 14V, 10% of OUT rising to end of blanking		80	ns	25.1, 25.4, 25.7
t _{on_min}	Minimum on-time				165	ns	26.1 ,26.2, 26.3, 26.4
t _{off_min}	Minimum off-time				65	ns	26.5, 26.6, 26.7, 26.8

4 Applicable and Reference Documents

4.1 Applicable Documents

- Texas Instruments, [TPS7H502x-SEP Radiation-Hardness-Assured 1-MHz Current Mode PWM Controller with Integrated Gate Driver](#), data sheet.
- Texas Instruments, [TPS7H5020EVM-CVAL Evaluation Module User's Guide](#), EVM user's guide.

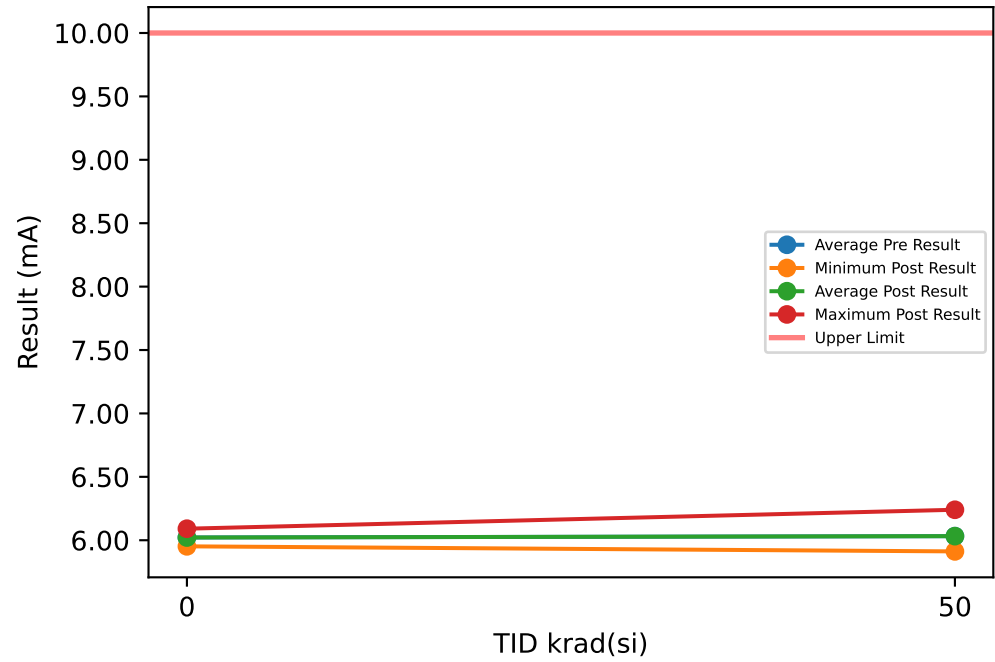
4.2 Reference Documents

Texas Instruments total ionizing dose radiation (total dose) test procedure follows the standards put forth in MIL-STD-883 TM 1019. The document can be found at the DLA website.

A Appendix: HDR TID Report

Device Test: 14.1 IDD_ACT_100K_NOLOAD(IDD|SUPPLY CURRENT/IN/4.5/4.5/0/0/4.5/100kHz//@IDD_ACT_100K_NOLOAD

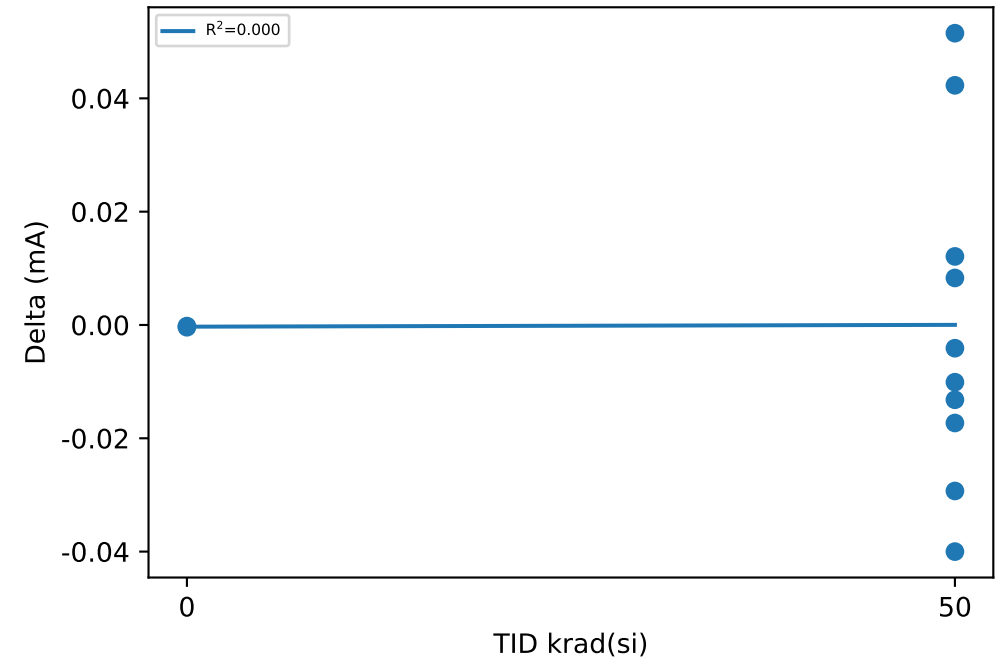
TID vs Result Stats



Test Results (Upper Limit = 10.0 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	6.0912	6.091	-0.0002
2	0	Correlation	5.9523	5.9519	-0.0004
4	50	Bias	6.0932	6.0759	-0.0173
6	50	Bias	6.0102	5.9702	-0.04
7	50	Bias	6.0144	6.0043	-0.0101
8	50	Bias	6.0864	6.0823	-0.0041
9	50	Bias	6.0377	6.0245	-0.0132
11	50	Unbias	5.9663	5.9746	0.0083
12	50	Unbias	5.9413	5.912	-0.0293
13	50	Unbias	5.9752	6.0267	0.0515
14	50	Unbias	5.9991	6.0112	0.0121
15	50	Unbias	6.198	6.2403	0.0423

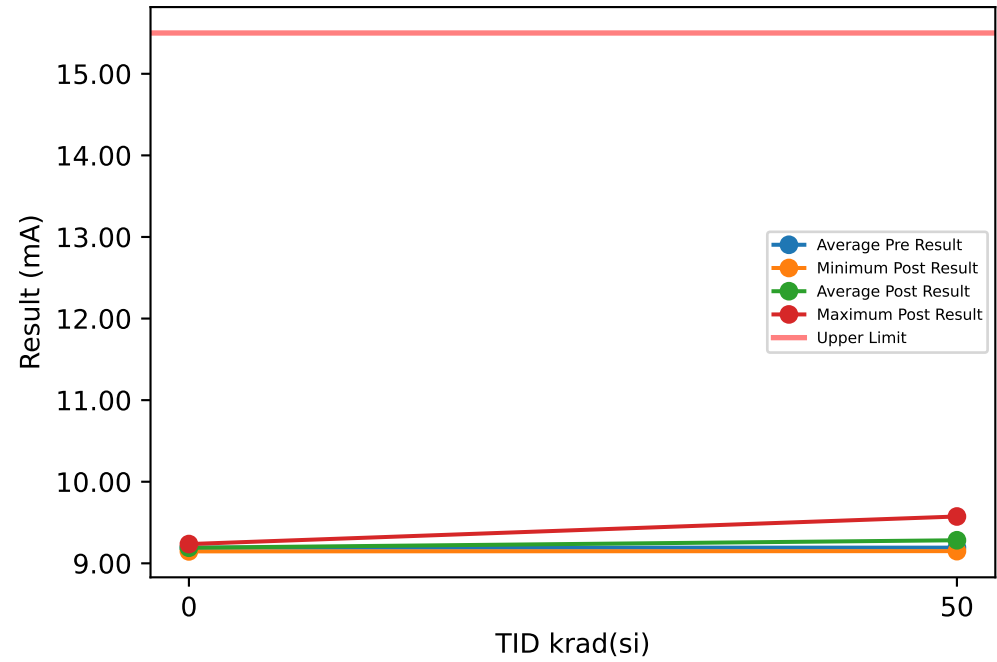
TID vs Post - Pre Exposure Delta



Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.9523	6.0217	6.0912	0.098217	5.9519	6.0214	6.091	0.098359	-0.0004	-0.0003	-0.0002	0.00014142
50	5.9413	6.0322	6.198	0.07596	5.912	6.0322	6.2403	0.088597	-0.04	2e-05	0.0515	0.029264

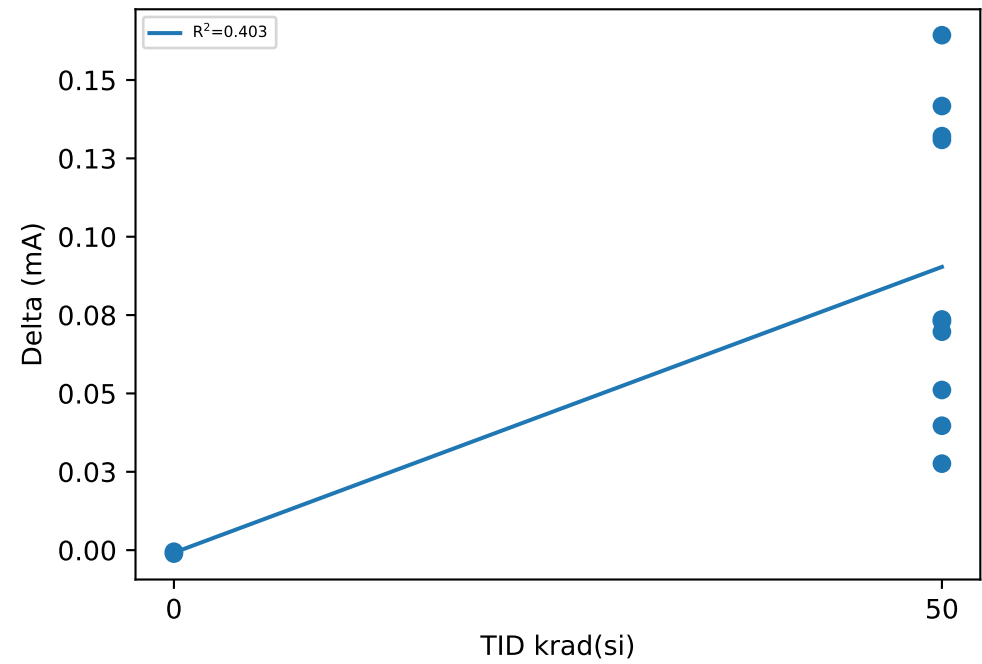
TID vs Result Stats



Test Results (Upper Limit = 15.5 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	9.2366	9.2361	-0.0005
2	0	Correlation	9.1473	9.1462	-0.0011
4	50	Bias	9.2286	9.2797	0.0511
6	50	Bias	9.1976	9.2373	0.0397
7	50	Bias	9.1276	9.1973	0.0697
8	50	Bias	9.1921	9.2657	0.0736
9	50	Bias	9.1439	9.2169	0.073
11	50	Unbias	9.2278	9.3599	0.1321
12	50	Unbias	9.1217	9.1493	0.0276
13	50	Unbias	9.1507	9.2816	0.1309
14	50	Unbias	9.1232	9.2649	0.1417
15	50	Unbias	9.4097	9.574	0.1643

TID vs Post - Pre Exposure Delta

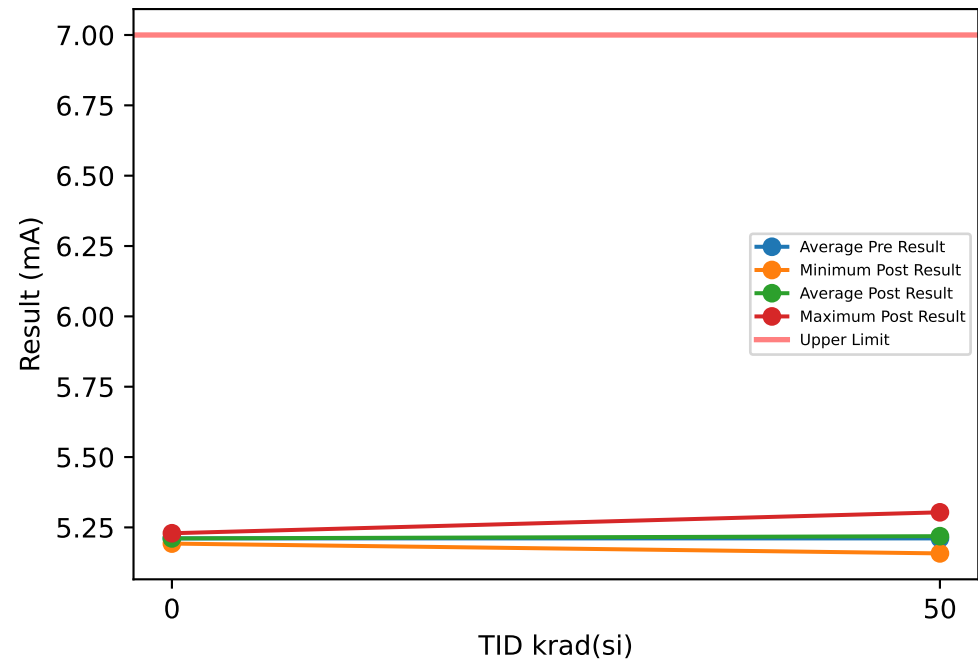


Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.1473	9.192	9.2366	0.063145	9.1462	9.1912	9.2361	0.063569	-0.0011	-0.0008	-0.0005	0.00042426
50	9.1217	9.1923	9.4097	0.086851	9.1493	9.2827	9.574	0.11686	0.0276	0.09037	0.1643	0.047778

Device Test: 14.11 IDD_DIS(IDD_DIS|STANDBY CURRENT/IN/12/12/0/0/5/500kHz//@IDD_DIS)

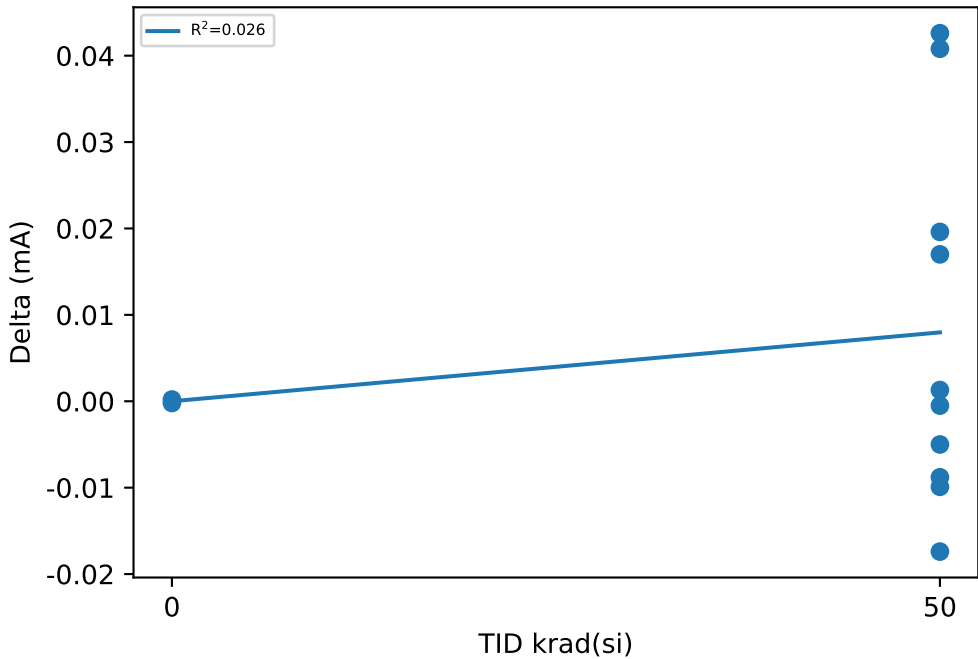
TID vs Result Stats



Test Results (Upper Limit = 7.0 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.229	5.2292	0.0002
2	0	Correlation	5.1927	5.1925	-0.0002
4	50	Bias	5.2282	5.2194	-0.0088
6	50	Bias	5.2327	5.2153	-0.0174
7	50	Bias	5.203	5.198	-0.005
8	50	Bias	5.2025	5.202	-0.0005
9	50	Bias	5.2309	5.2322	0.0013
11	50	Unbias	5.2081	5.2251	0.017
12	50	Unbias	5.1675	5.1576	-0.0099
13	50	Unbias	5.1775	5.2201	0.0426
14	50	Unbias	5.1951	5.2147	0.0196
15	50	Unbias	5.2628	5.3036	0.0408

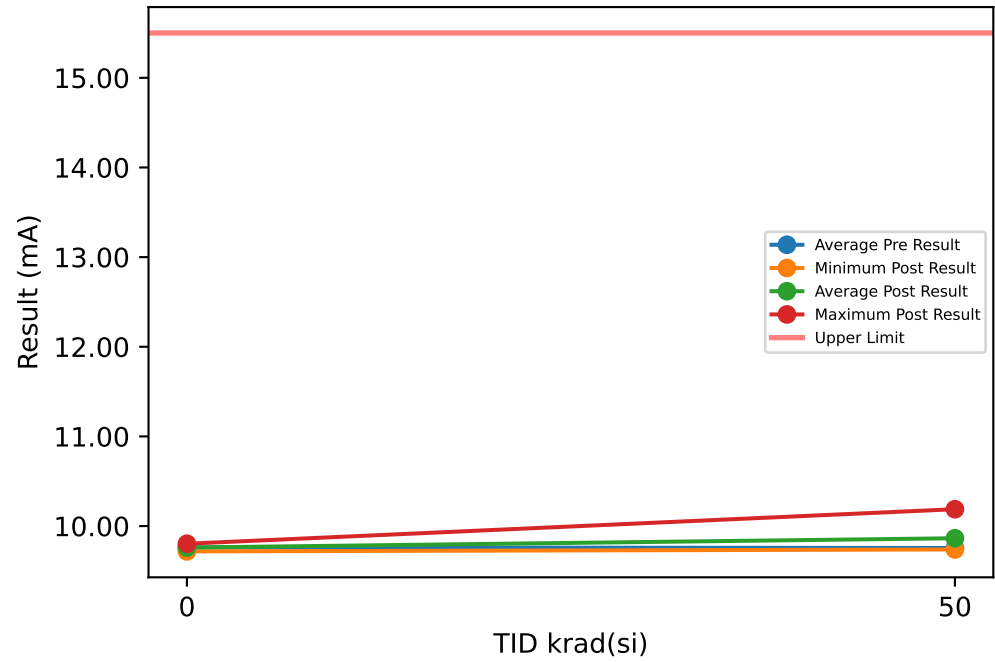
TID vs Post - Pre Exposure Delta



Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.1927	5.2108	5.229	0.025668	5.1925	5.2108	5.2292	0.025951	-0.0002	0	0.0002	0.00028284
50	5.1675	5.2108	5.2628	0.028397	5.1576	5.2188	5.3036	0.036365	-0.0174	0.00797	0.0426	0.021141

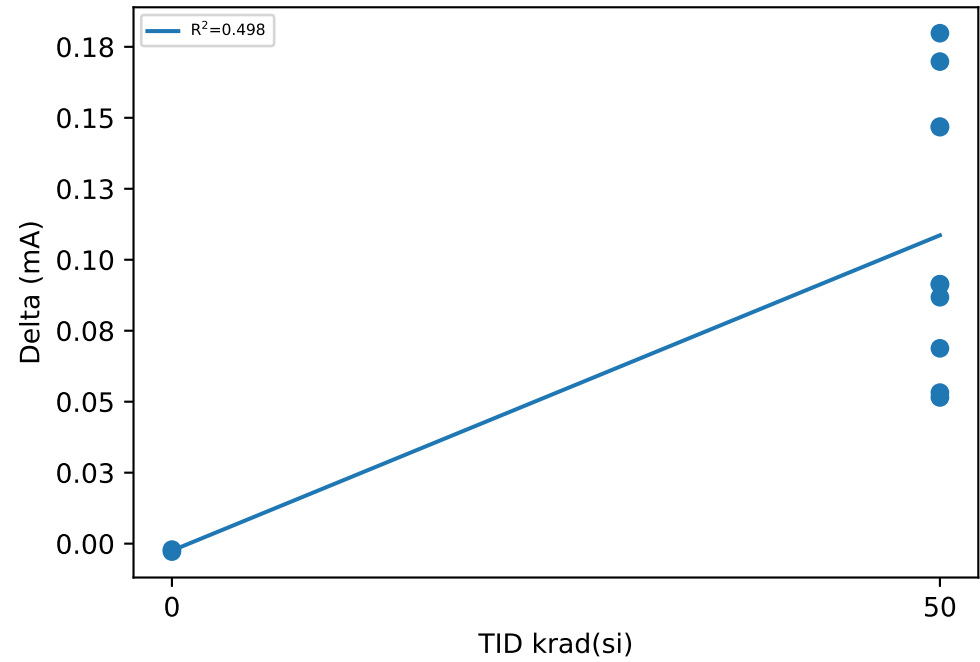
TID vs Result Stats



Test Results (Upper Limit = 15.5 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	9.805	9.8029	-0.0021
2	0	Correlation	9.7203	9.7175	-0.0028
4	50	Bias	9.802	9.8708	0.0688
6	50	Bias	9.7485	9.8017	0.0532
7	50	Bias	9.6768	9.7636	0.0868
8	50	Bias	9.7508	9.8421	0.0913
9	50	Bias	9.6879	9.7793	0.0914
11	50	Unbias	9.8154	9.9621	0.1467
12	50	Unbias	9.6875	9.739	0.0515
13	50	Unbias	9.7131	9.86	0.1469
14	50	Unbias	9.6657	9.8355	0.1698
15	50	Unbias	10.008	10.188	0.1798

TID vs Post - Pre Exposure Delta

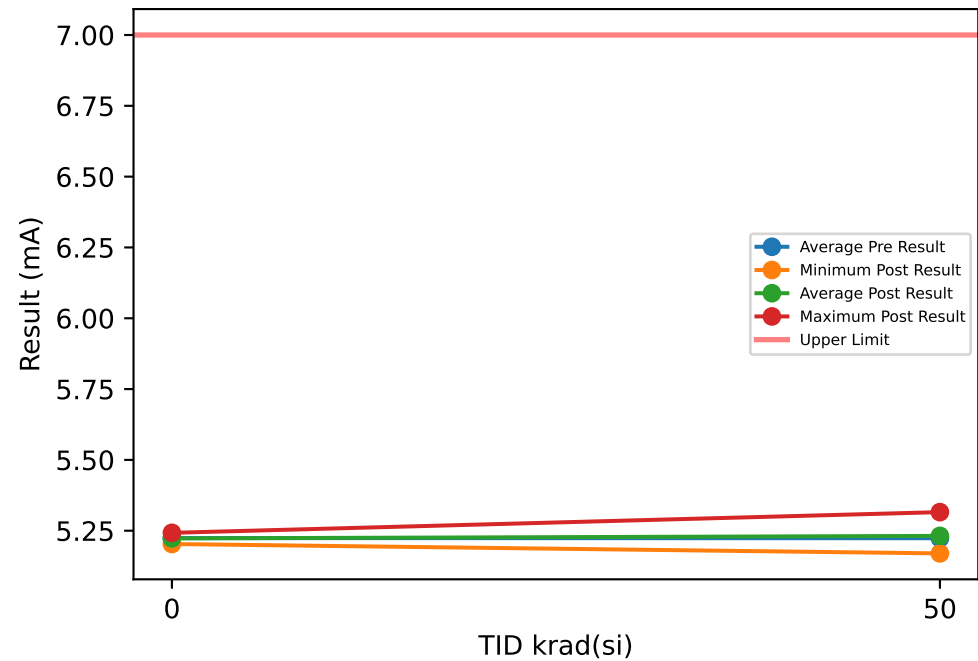


Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.7203	9.7627	9.805	0.059892	9.7175	9.7602	9.8029	0.060387	-0.0028	-0.00245	-0.0021	0.00049497
50	9.6657	9.7556	10.008	0.1027	9.739	9.8642	10.188	0.13026	0.0515	0.10862	0.1798	0.047978

Device Test: 14.13 IDD_DIS(IDD_DIS|STANDBY CURRENT/IN/14/14/0/0/5/500kHz//@IDD_DIS)

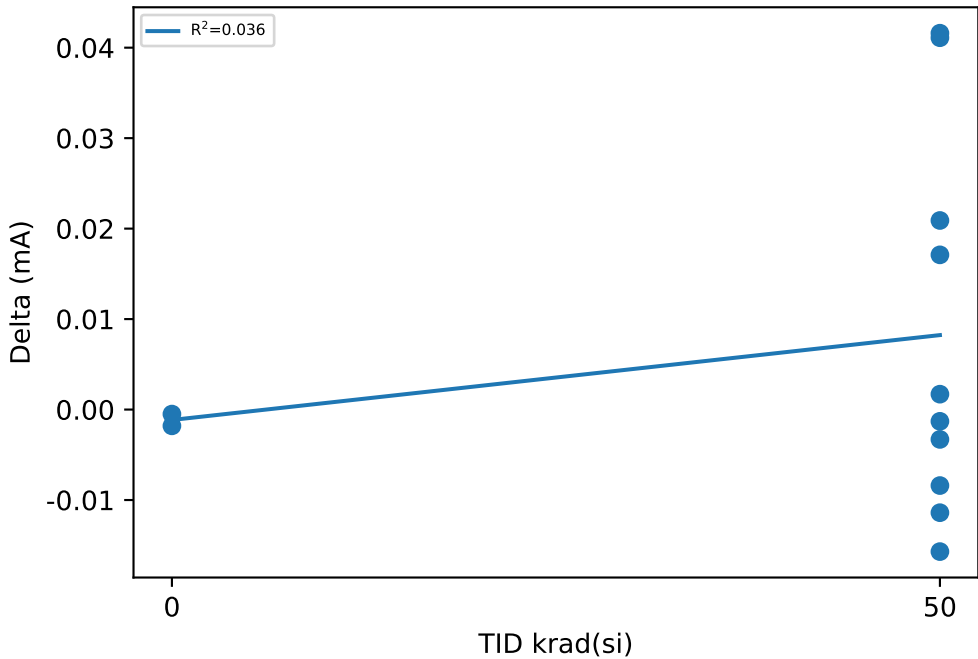
TID vs Result Stats



Test Results (Upper Limit = 7.0 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.243	5.2425	-0.0005
2	0	Correlation	5.2048	5.203	-0.0018
4	50	Bias	5.2416	5.2332	-0.0084
6	50	Bias	5.2452	5.2295	-0.0157
7	50	Bias	5.215	5.2117	-0.0033
8	50	Bias	5.214	5.2127	-0.0013
9	50	Bias	5.2435	5.2452	0.0017
11	50	Unbias	5.2218	5.2389	0.0171
12	50	Unbias	5.1813	5.1699	-0.0114
13	50	Unbias	5.192	5.2331	0.0411
14	50	Unbias	5.2061	5.227	0.0209
15	50	Unbias	5.274	5.3156	0.0416

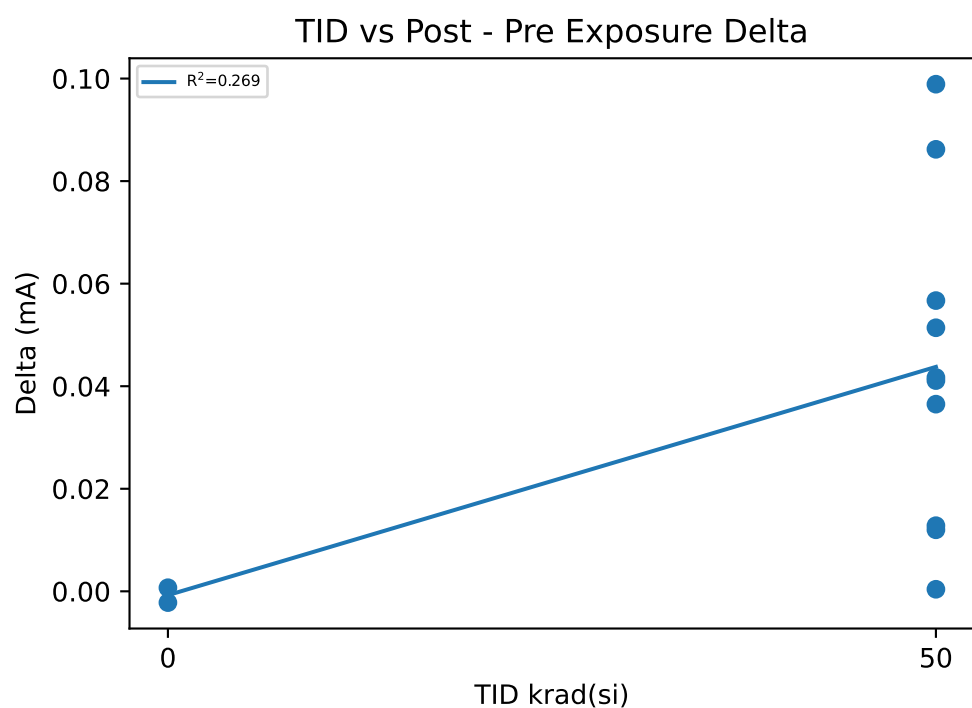
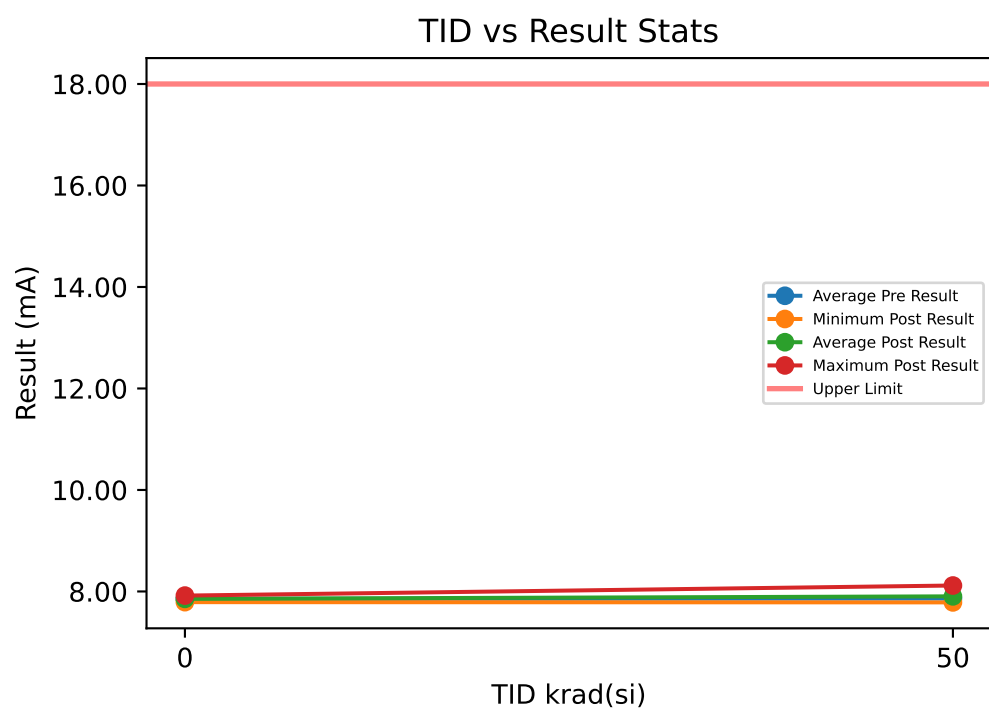
TID vs Post - Pre Exposure Delta



Test Statistics (mA)

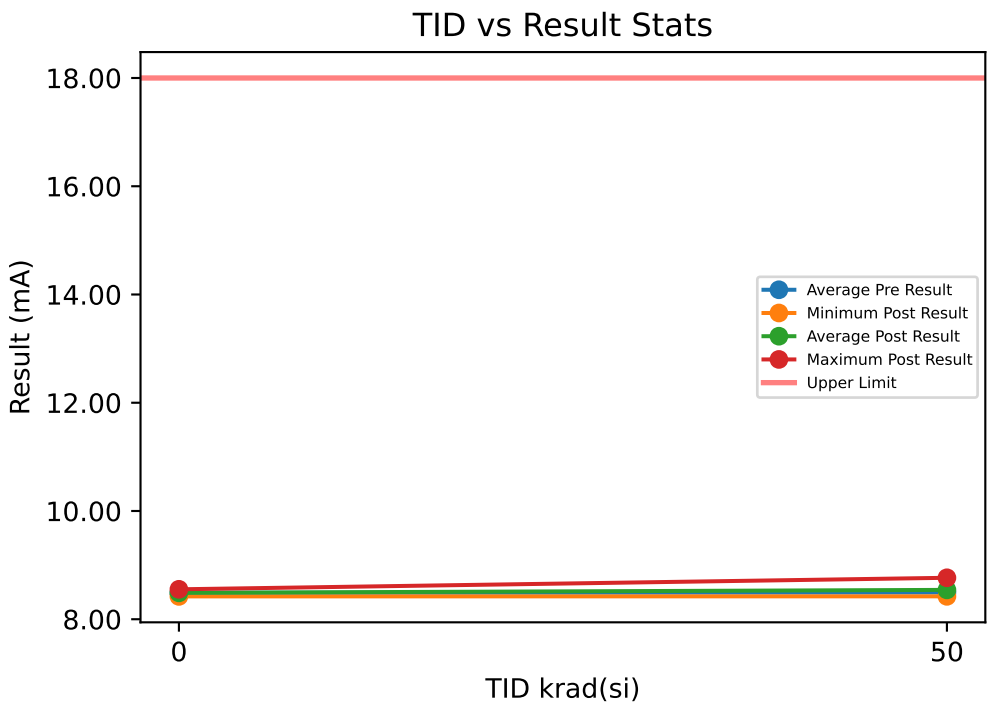
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.2048	5.2239	5.243	0.027011	5.203	5.2227	5.2425	0.027931	-0.0018	-0.00115	-0.0005	0.00091924
50	5.1813	5.2234	5.274	0.027869	5.1699	5.2317	5.3156	0.036339	-0.0157	0.00823	0.0416	0.020908

Device Test: 14.14 IDD_ACT_1M_NOLOAD(IDD|SUPPLY CURRENT/IN/4.5/4.5/0/0/4.5/1MHz//@IDD_ACT_1M_NOLOAD



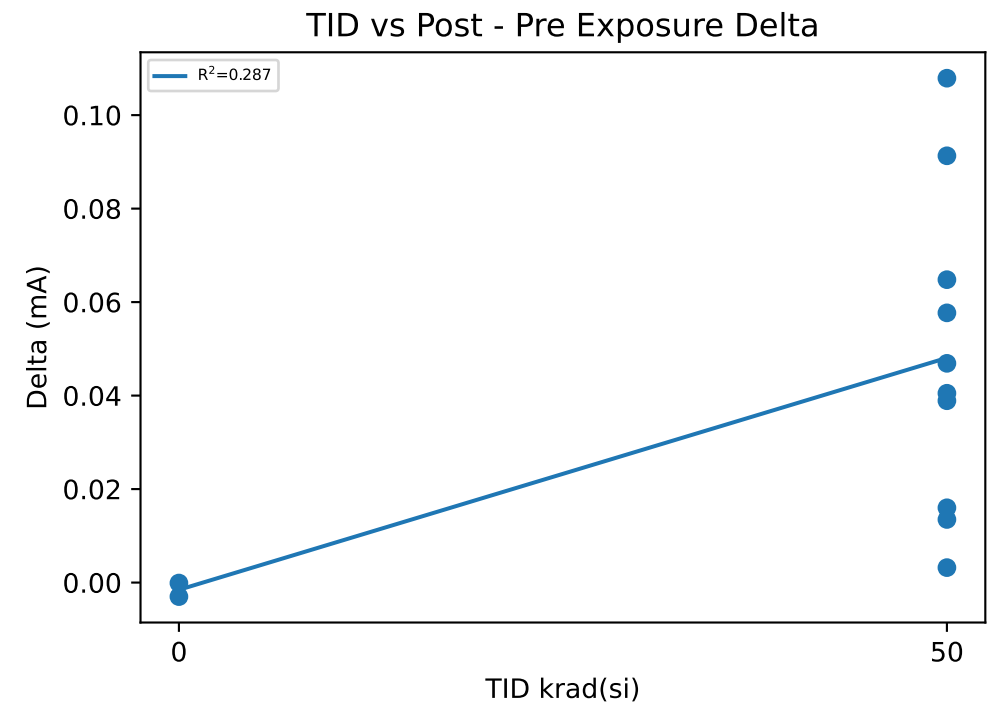
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.921	7.9188	-0.0022
2	0	Correlation	7.7887	7.7894	0.0007
4	50	Bias	7.9506	7.9626	0.012
6	50	Bias	7.822	7.8224	0.0004
7	50	Bias	7.8397	7.8814	0.0417
8	50	Bias	7.8988	7.9399	0.0411
9	50	Bias	7.8417	7.8782	0.0365
11	50	Unbias	7.8078	7.8592	0.0514
12	50	Unbias	7.7717	7.7845	0.0128
13	50	Unbias	7.8117	7.9106	0.0989
14	50	Unbias	7.8264	7.8831	0.0567
15	50	Unbias	8.031	8.1172	0.0862

	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.7887	7.8548	7.921	0.09355	7.7894	7.8541	7.9188	0.0915	-0.0022	-0.00075	0.0007	0.0020506
50	7.7717	7.8601	8.031	0.078265	7.7845	7.9039	8.1172	0.091153	0.0004	0.04377	0.0989	0.031585



Test Results (Upper Limit = 18.0 (mA))

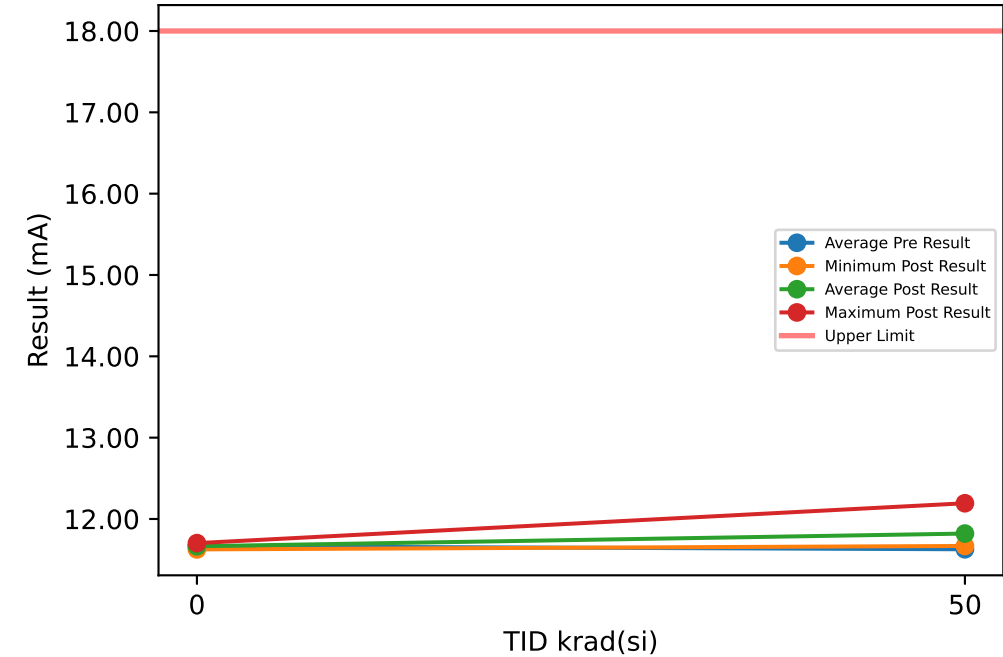
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	8.5561	8.5531	-0.003
2	0	Correlation	8.4221	8.422	-0.0001
4	50	Bias	8.5951	8.6086	0.0135
6	50	Bias	8.4533	8.4565	0.0032
7	50	Bias	8.47	8.5105	0.0405
8	50	Bias	8.5301	8.577	0.0469
9	50	Bias	8.471	8.5099	0.0389
11	50	Unbias	8.4423	8.5	0.0577
12	50	Unbias	8.4069	8.4229	0.016
13	50	Unbias	8.4441	8.552	0.1079
14	50	Unbias	8.456	8.5208	0.0648
15	50	Unbias	8.6745	8.7658	0.0913



Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.4221	8.4891	8.5561	0.094752	8.422	8.4875	8.5531	0.092702	-0.003	-0.00155	-0.0001	0.0020506
50	8.4069	8.4943	8.6745	0.082367	8.4229	8.5424	8.7658	0.095205	0.0032	0.04807	0.1079	0.033666

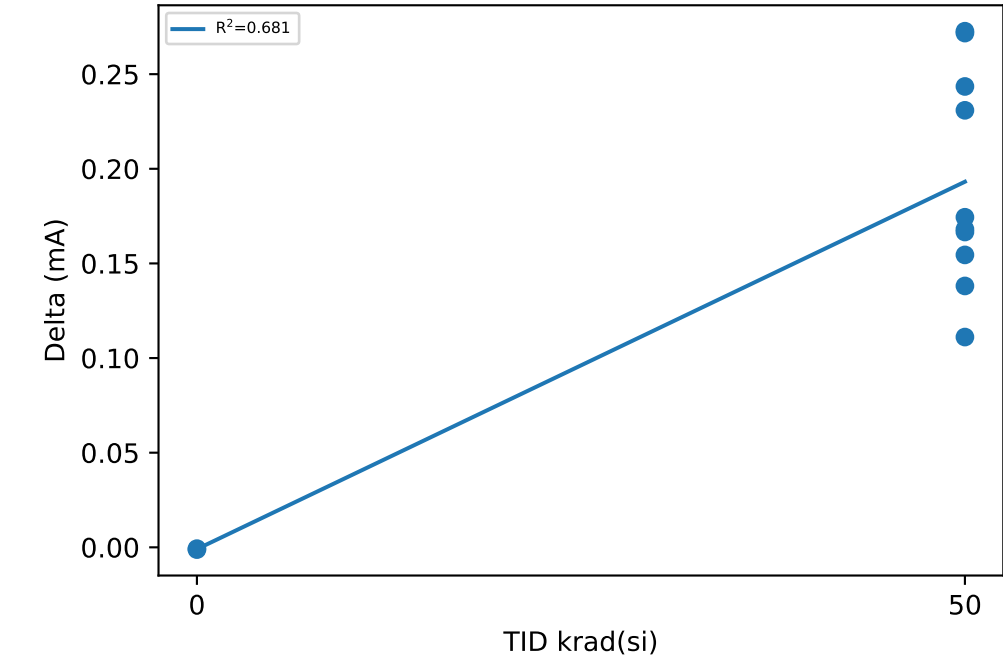
TID vs Result Stats



Test Results (Upper Limit = 18.0 (mA))

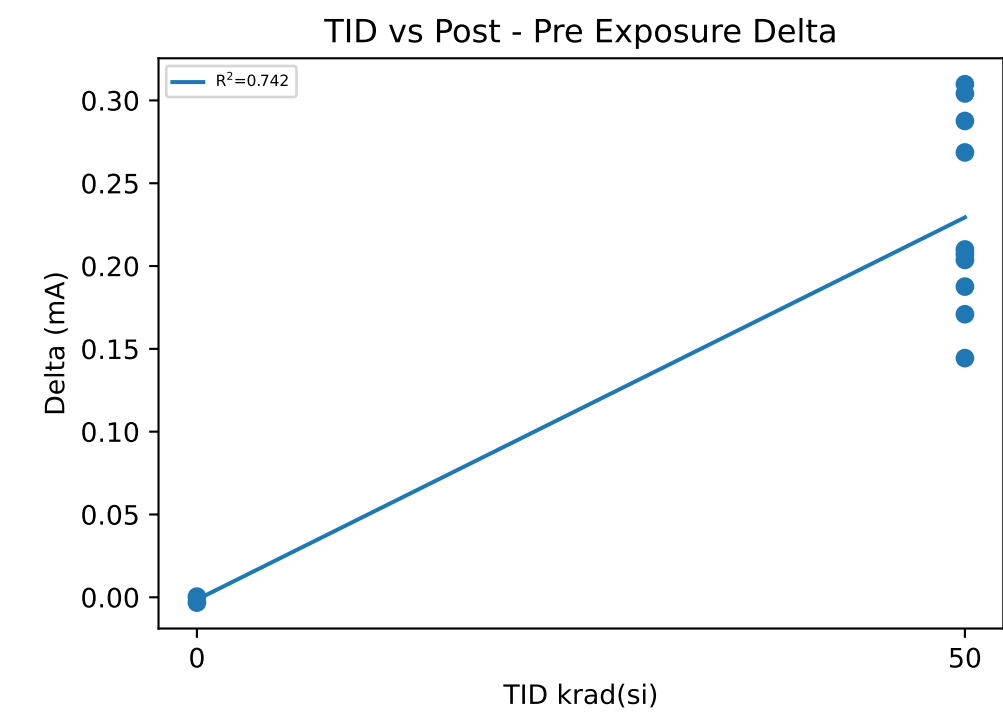
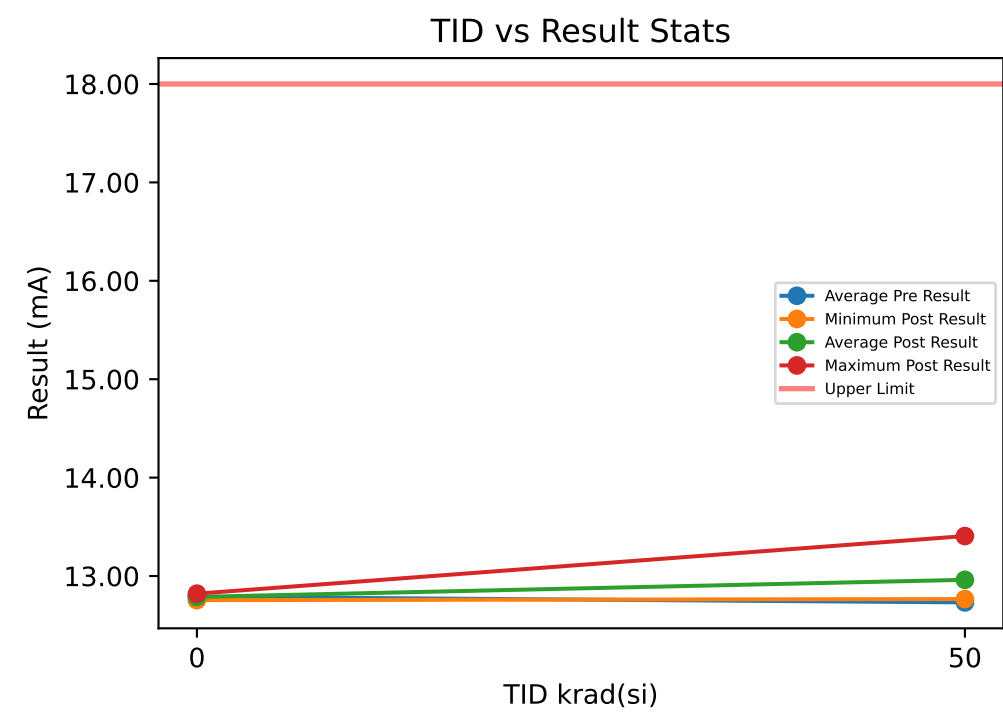
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	11.704	11.703	-0.0007
2	0	Correlation	11.627	11.626	-0.0012
4	50	Bias	11.687	11.825	0.1381
6	50	Bias	11.608	11.719	0.1111
7	50	Bias	11.569	11.724	0.1545
8	50	Bias	11.618	11.792	0.1744
9	50	Bias	11.502	11.668	0.1666
11	50	Unbias	11.709	11.94	0.2309
12	50	Unbias	11.536	11.704	0.1681
13	50	Unbias	11.596	11.869	0.2727
14	50	Unbias	11.528	11.772	0.2435
15	50	Unbias	11.922	12.193	0.2717

TID vs Post - Pre Exposure Delta



Test Statistics (mA)

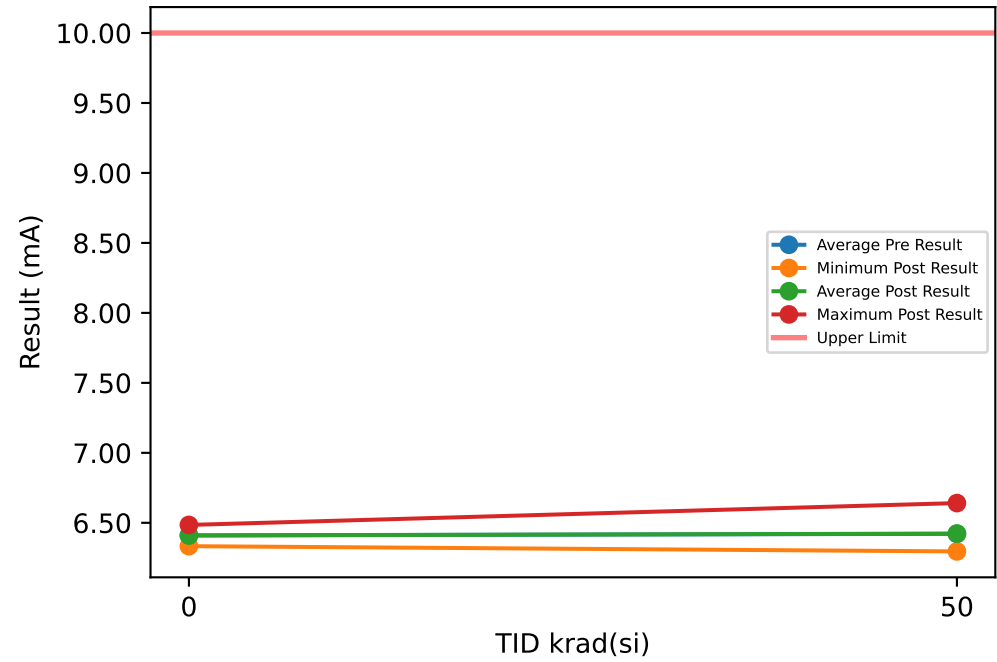
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.627	11.665	11.704	0.054094	11.626	11.665	11.703	0.054447	-0.0012	-0.00095	-0.0007	0.00035355
50	11.502	11.627	11.922	0.12268	11.668	11.821	12.193	0.15458	0.1111	0.19316	0.2727	0.057154



Test Results (Upper Limit = 18.0 (mA))					
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	12.82	12.82	0.0004
2	0	Correlation	12.758	12.755	-0.0032
4	50	Bias	12.807	12.978	0.1709
6	50	Bias	12.684	12.828	0.1444
7	50	Bias	12.643	12.831	0.1876
8	50	Bias	12.72	12.93	0.21
9	50	Bias	12.562	12.766	0.2037
11	50	Unbias	12.862	13.13	0.2686
12	50	Unbias	12.643	12.85	0.207
13	50	Unbias	12.705	13.009	0.3042
14	50	Unbias	12.598	12.886	0.2876
15	50	Unbias	13.096	13.406	0.3098

Test Statistics (mA)												
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.758	12.789	12.82	0.04377	12.755	12.788	12.82	0.046315	-0.0032	-0.0014	0.0004	0.0025456
50	12.562	12.732	13.096	0.15664	12.766	12.961	13.406	0.18885	0.1444	0.22938	0.3098	0.05861

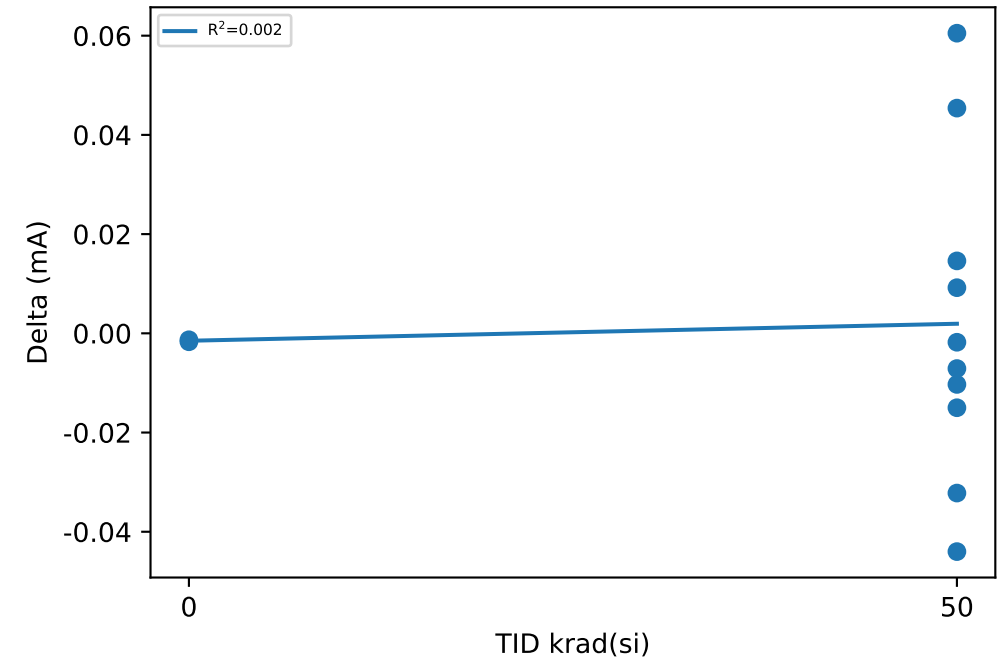
TID vs Result Stats



Test Results (Upper Limit = 10.0 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	6.4865	6.4848	-0.0017
2	0	Correlation	6.3343	6.333	-0.0013
4	50	Bias	6.4886	6.4736	-0.015
6	50	Bias	6.4011	6.3571	-0.044
7	50	Bias	6.4013	6.3942	-0.0071
8	50	Bias	6.4798	6.478	-0.0018
9	50	Bias	6.4227	6.4124	-0.0103
11	50	Unbias	6.3528	6.362	0.0092
12	50	Unbias	6.3279	6.2957	-0.0322
13	50	Unbias	6.3598	6.4203	0.0605
14	50	Unbias	6.3817	6.3963	0.0146
15	50	Unbias	6.5955	6.6409	0.0454

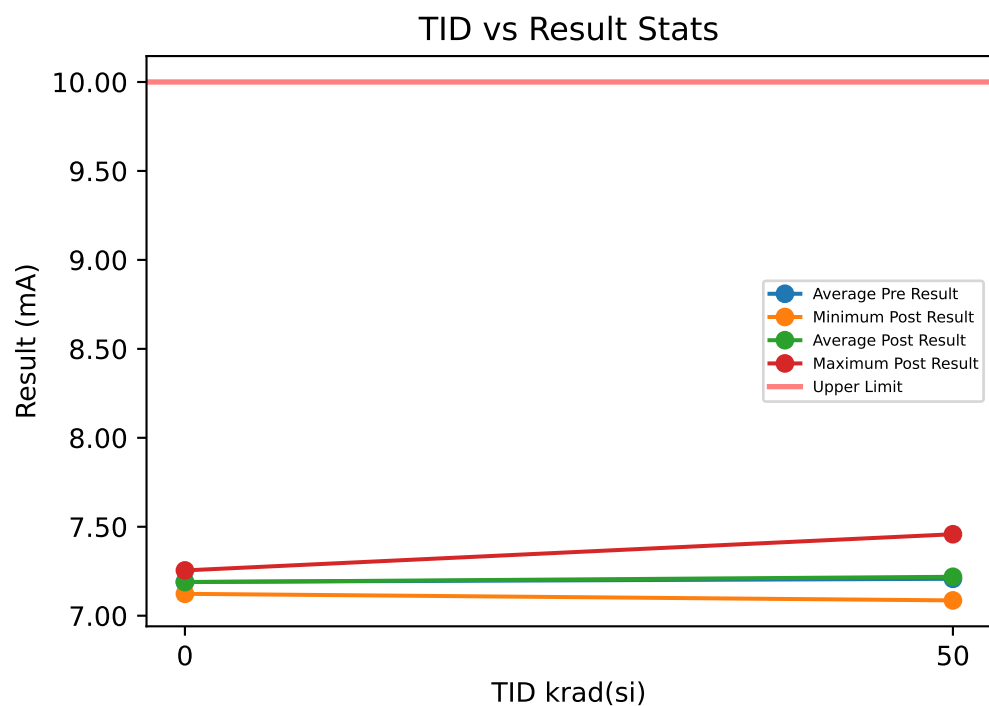
TID vs Post - Pre Exposure Delta



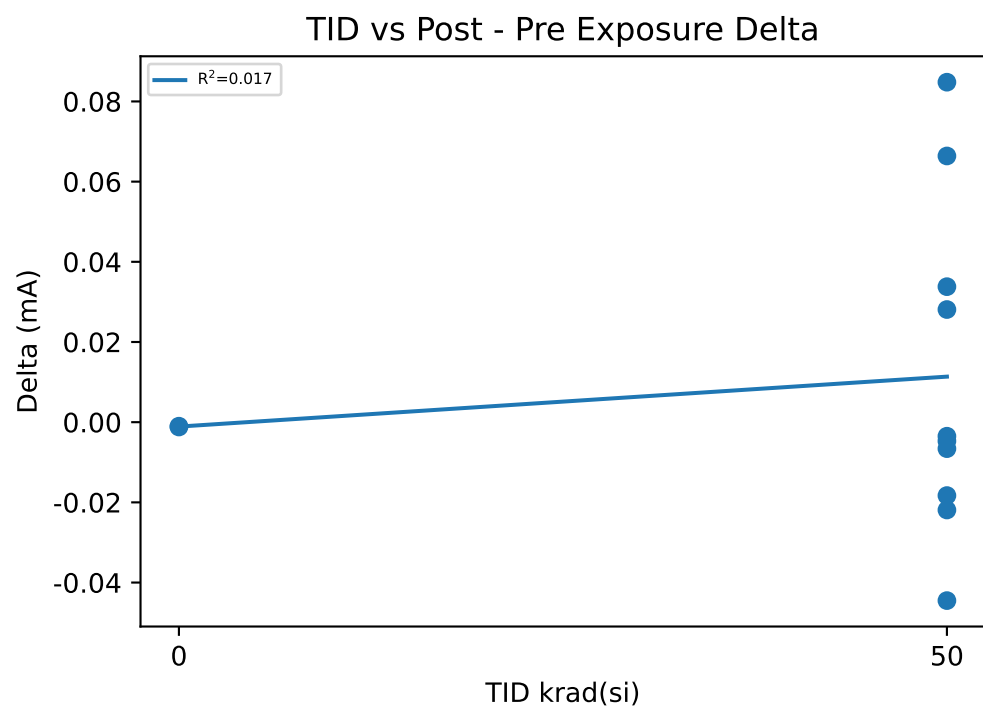
Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.3343	6.4104	6.4865	0.10762	6.333	6.4089	6.4848	0.10734	-0.0017	-0.0015	-0.0013	0.00028284
50	6.3279	6.4211	6.5955	0.080189	6.2957	6.4231	6.6409	0.093688	-0.044	0.00193	0.0605	0.032214

Device Test: 14.3 IDD_ACT_100K_NOLOAD(IDD|SUPPLY CURRENT/IN/12/12/0/0/5/100kHz//@IDD_ACT_100K_NOLOAD

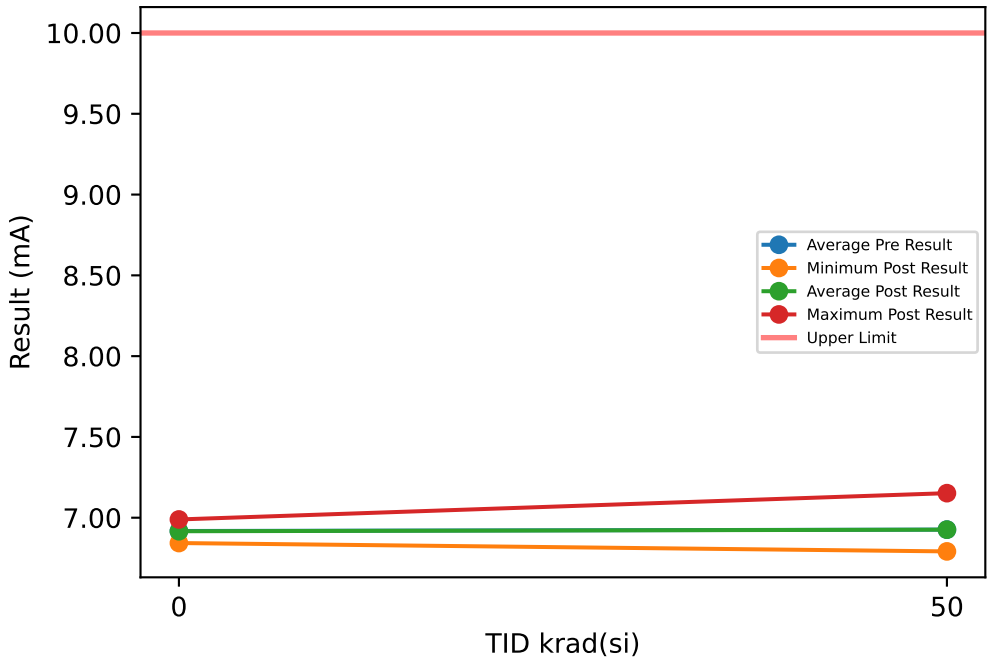


Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.2556	7.2546	-0.001
2	0	Correlation	7.1242	7.123	-0.0012
4	50	Bias	7.2822	7.2639	-0.0183
6	50	Bias	7.2252	7.1807	-0.0445
7	50	Bias	7.172	7.1685	-0.0035
8	50	Bias	7.243	7.2364	-0.0066
9	50	Bias	7.2082	7.2035	-0.0047
11	50	Unbias	7.1796	7.2077	0.0281
12	50	Unbias	7.108	7.0861	-0.0219
13	50	Unbias	7.1241	7.2089	0.0848
14	50	Unbias	7.1405	7.1743	0.0338
15	50	Unbias	7.3915	7.4579	0.0664



krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.1242	7.1899	7.2556	0.092914	7.123	7.1888	7.2546	0.093055	-0.0012	-0.0011	-0.001	0.00014142
50	7.108	7.2074	7.3915	0.084586	7.0861	7.2188	7.4579	0.096344	-0.0445	0.01136	0.0848	0.04098

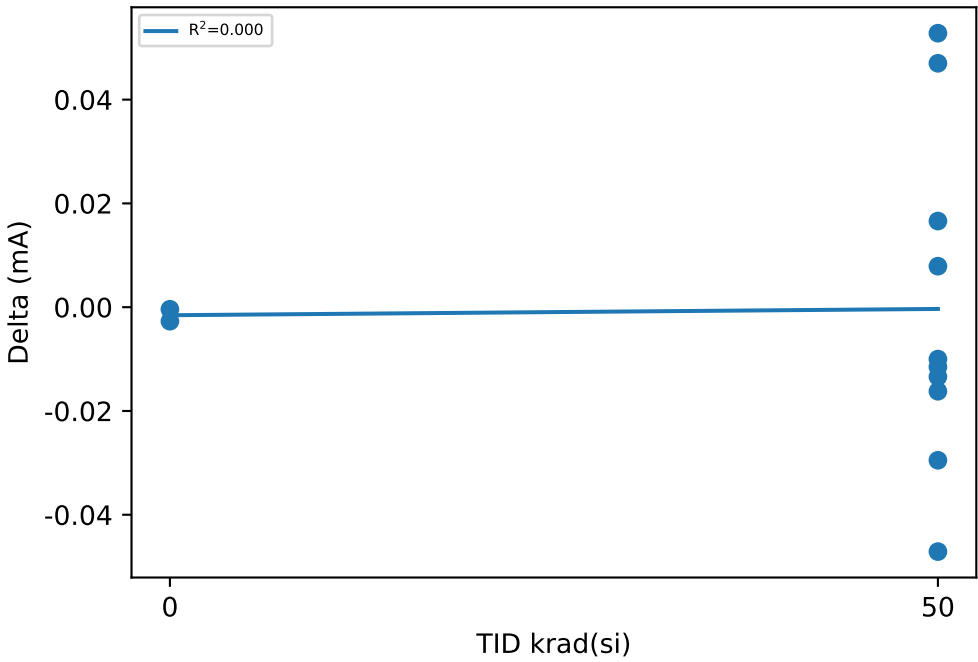
TID vs Result Stats



Test Results (Upper Limit = 10.0 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	6.9896	6.9892	-0.0004
2	0	Correlation	6.8459	6.8432	-0.0027
4	50	Bias	7.0023	6.9889	-0.0134
6	50	Bias	6.9069	6.8598	-0.0471
7	50	Bias	6.9136	6.9036	-0.01
8	50	Bias	6.982	6.9705	-0.0115
9	50	Bias	6.9376	6.9214	-0.0162
11	50	Unbias	6.8564	6.8643	0.0079
12	50	Unbias	6.821	6.7915	-0.0295
13	50	Unbias	6.8658	6.9186	0.0528
14	50	Unbias	6.8734	6.89	0.0166
15	50	Unbias	7.1049	7.1519	0.047

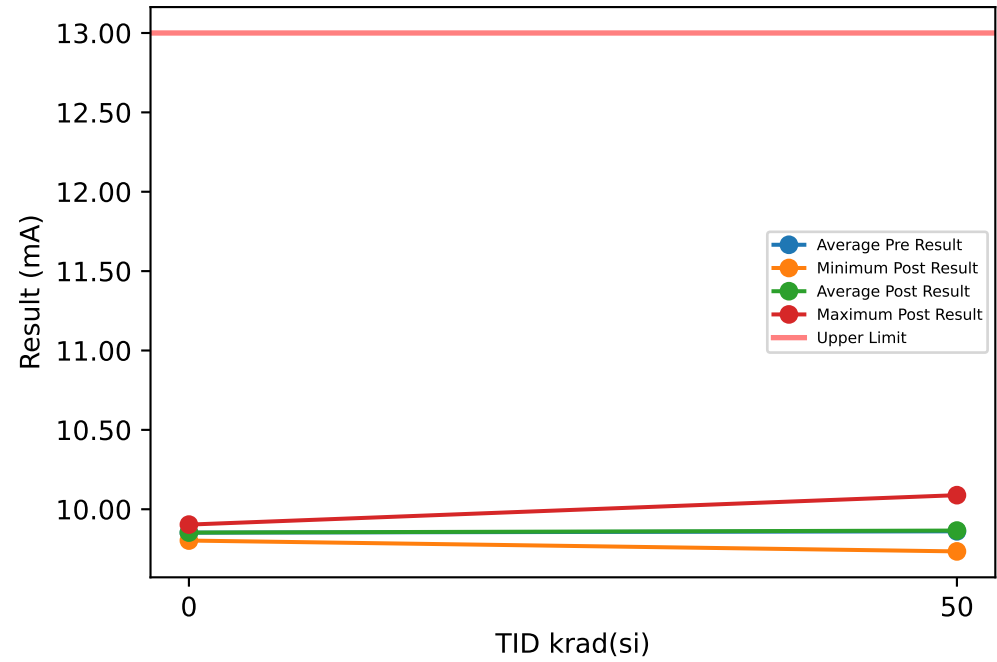
TID vs Post - Pre Exposure Delta



Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.8459	6.9177	6.9896	0.10161	6.8432	6.9162	6.9892	0.10324	-0.0027	-0.00155	-0.0004	0.0016263
50	6.821	6.9264	7.1049	0.084245	6.7915	6.9261	7.1519	0.097252	-0.0471	-0.00034	0.0528	0.031792

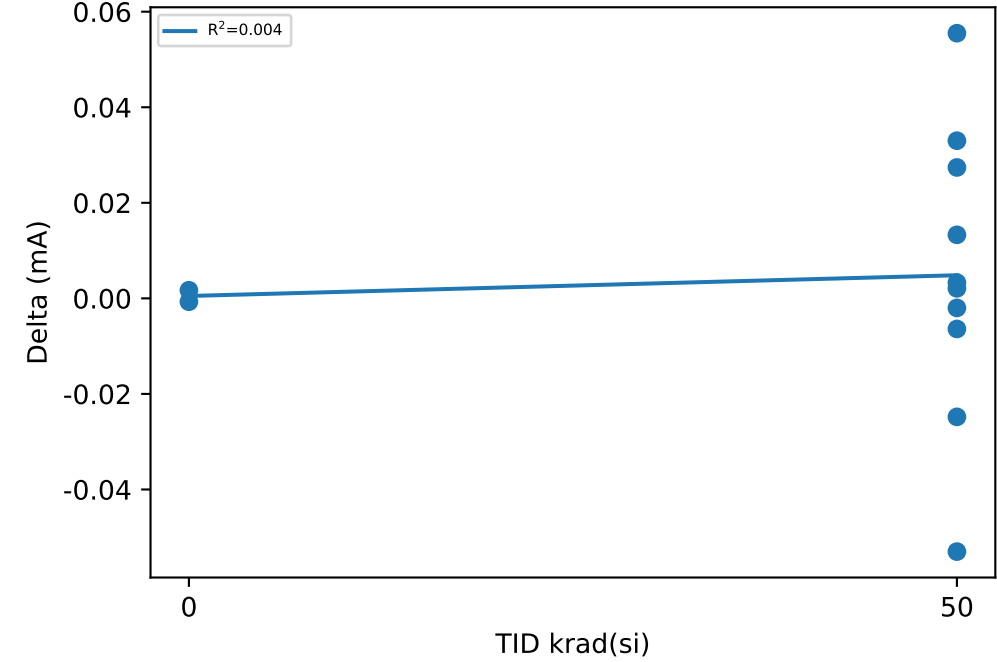
TID vs Result Stats



Test Results (Upper Limit = 13.0 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	9.904	9.9033	-0.0007
2	0	Correlation	9.8011	9.8028	0.0017
4	50	Bias	9.9309	9.9245	-0.0064
6	50	Bias	9.8127	9.7879	-0.0248
7	50	Bias	9.8253	9.8274	0.0021
8	50	Bias	9.8735	9.8768	0.0033
9	50	Bias	9.8736	9.8716	-0.002
11	50	Unbias	9.8377	9.8651	0.0274
12	50	Unbias	9.7875	9.7345	-0.053
13	50	Unbias	9.832	9.8453	0.0133
14	50	Unbias	9.8029	9.8359	0.033
15	50	Unbias	10.033	10.089	0.0555

TID vs Post - Pre Exposure Delta

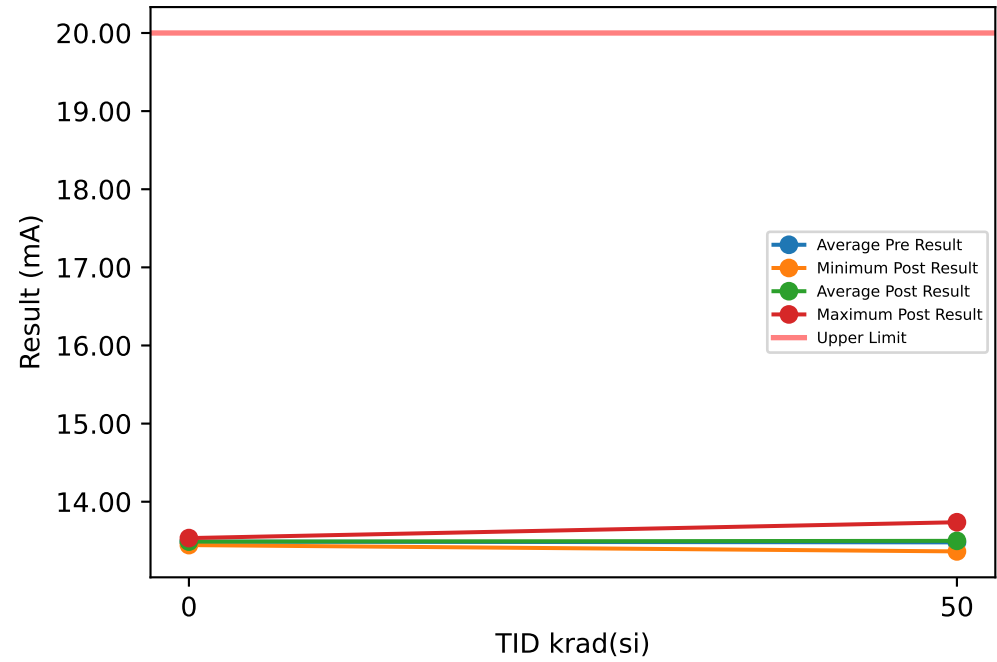


Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.8011	9.8526	9.904	0.072761	9.8028	9.853	9.9033	0.071064	-0.0007	0.0005	0.0017	0.0016971
50	9.7875	9.8609	10.033	0.073502	9.7345	9.8658	10.089	0.093916	-0.053	0.00484	0.0555	0.030454

Device Test: 14.32 IDD_ACT_1M_LOAD_LDO(IDD|SUPPLY CURRENT|IN/5/12/0/1000/5/1MHz//@IDD_ACT_1M_LOAD_LD

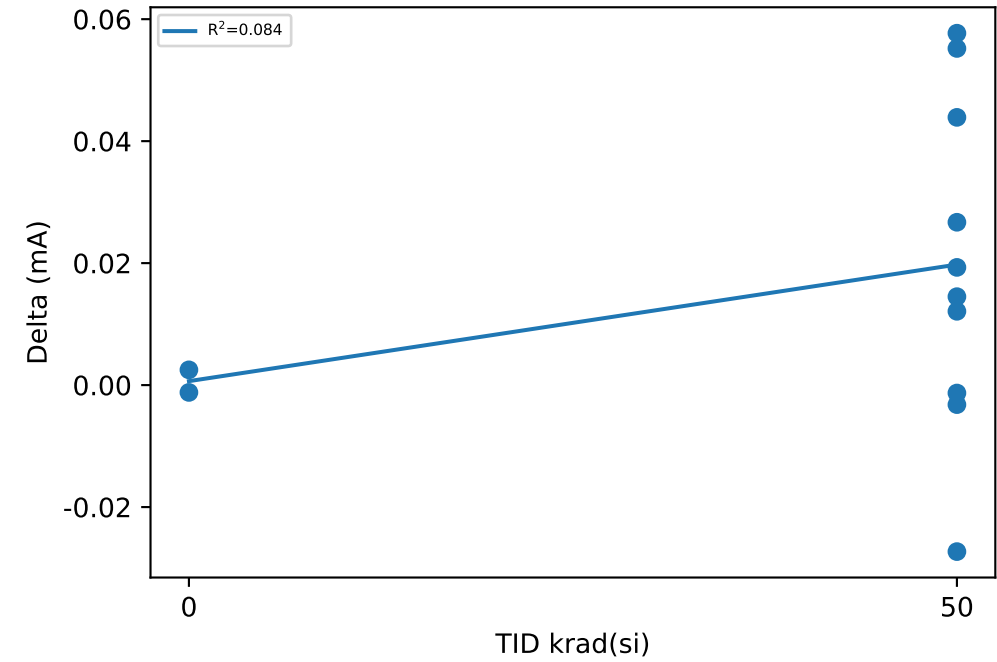
TID vs Result Stats



Test Results (Upper Limit = 20.0 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	13.536	13.534	-0.0012
2	0	Correlation	13.442	13.445	0.0025
4	50	Bias	13.61	13.608	-0.0013
6	50	Bias	13.391	13.364	-0.0273
7	50	Bias	13.459	13.471	0.0121
8	50	Bias	13.474	13.493	0.0193
9	50	Bias	13.477	13.491	0.0145
11	50	Unbias	13.476	13.503	0.0267
12	50	Unbias	13.393	13.39	-0.0032
13	50	Unbias	13.448	13.503	0.0552
14	50	Unbias	13.386	13.43	0.0439
15	50	Unbias	13.68	13.737	0.0577

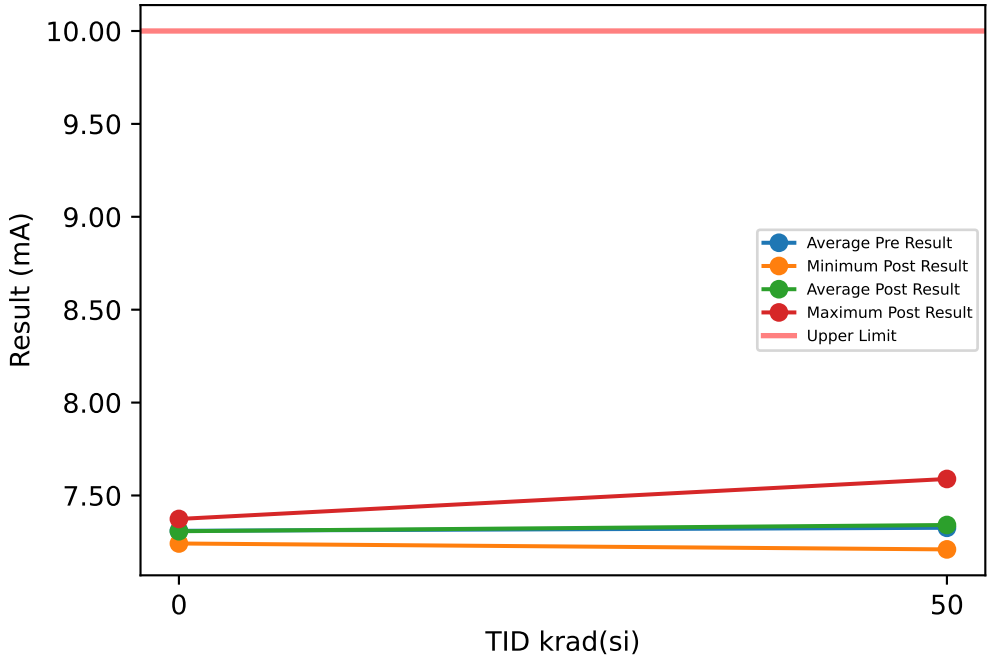
TID vs Post - Pre Exposure Delta



Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	13.442	13.489	13.536	0.065973	13.445	13.49	13.534	0.063357	-0.0012	0.00065	0.0025	0.0026163
50	13.386	13.479	13.68	0.095687	13.364	13.499	13.737	0.10777	-0.0273	0.01976	0.0577	0.027076

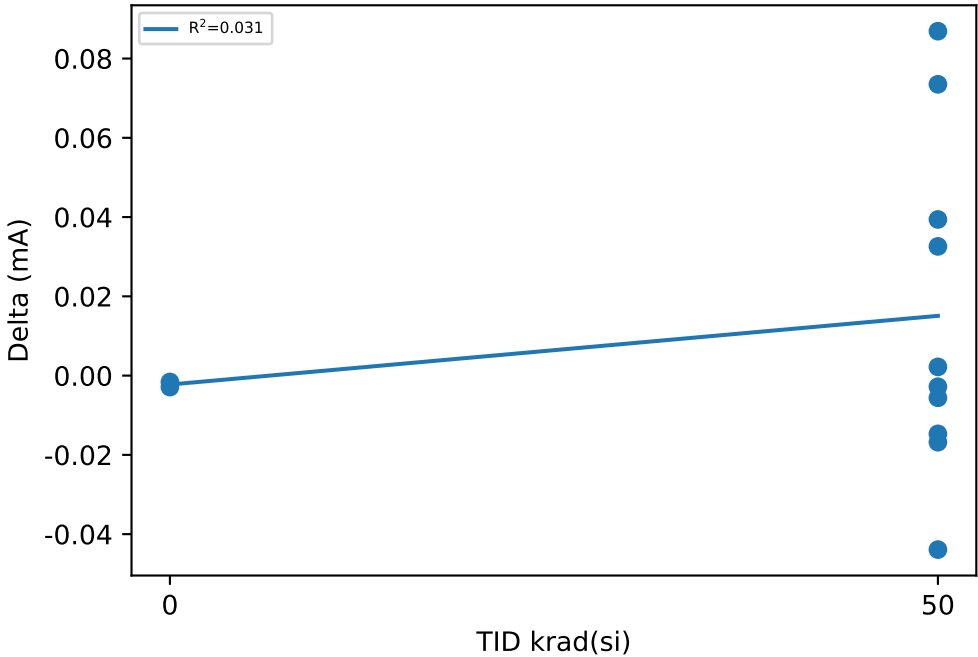
TID vs Result Stats



Test Results (Upper Limit = 10.0 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.3765	7.3736	-0.0029
2	0	Correlation	7.2432	7.2416	-0.0016
4	50	Bias	7.4036	7.3889	-0.0147
6	50	Bias	7.3415	7.2976	-0.0439
7	50	Bias	7.2887	7.2859	-0.0028
8	50	Bias	7.3606	7.355	-0.0056
9	50	Bias	7.3221	7.3243	0.0022
11	50	Unbias	7.3039	7.3365	0.0326
12	50	Unbias	7.2266	7.2098	-0.0168
13	50	Unbias	7.2433	7.3302	0.0869
14	50	Unbias	7.2547	7.2941	0.0394
15	50	Unbias	7.5154	7.5889	0.0735

TID vs Post - Pre Exposure Delta

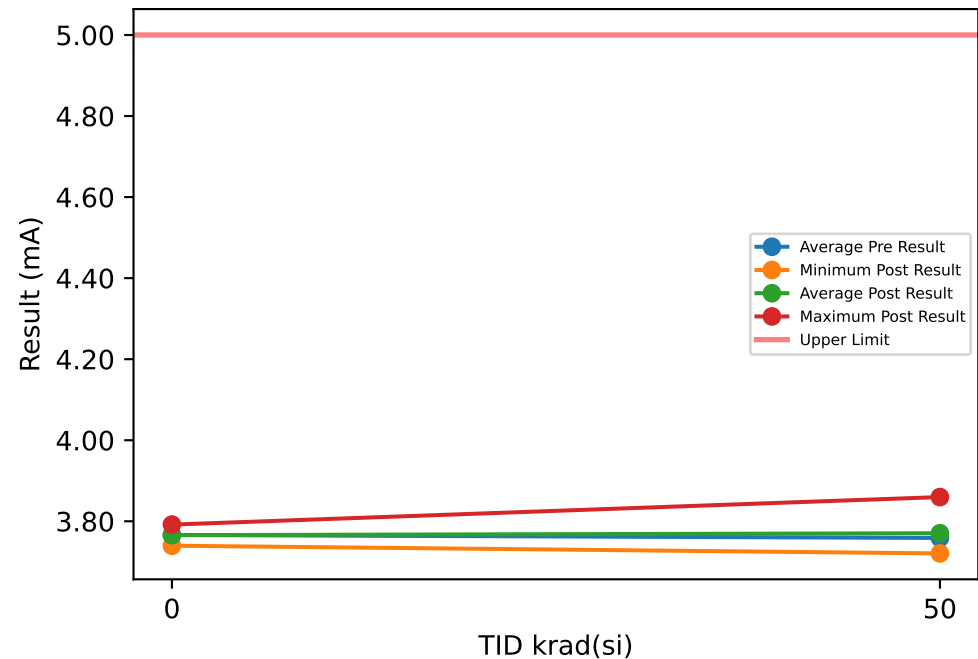


Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.2432	7.3098	7.3765	0.094257	7.2416	7.3076	7.3736	0.093338	-0.0029	-0.00225	-0.0016	0.00091924
50	7.2266	7.326	7.5154	0.0863	7.2098	7.3411	7.5889	0.099271	-0.0439	0.01508	0.0869	0.041852

Device Test: 14.5 I_START(ISTART|STARTUP CURRENT/IN/3.5/3.5/0/0/4.5/500kHz//@I_START)

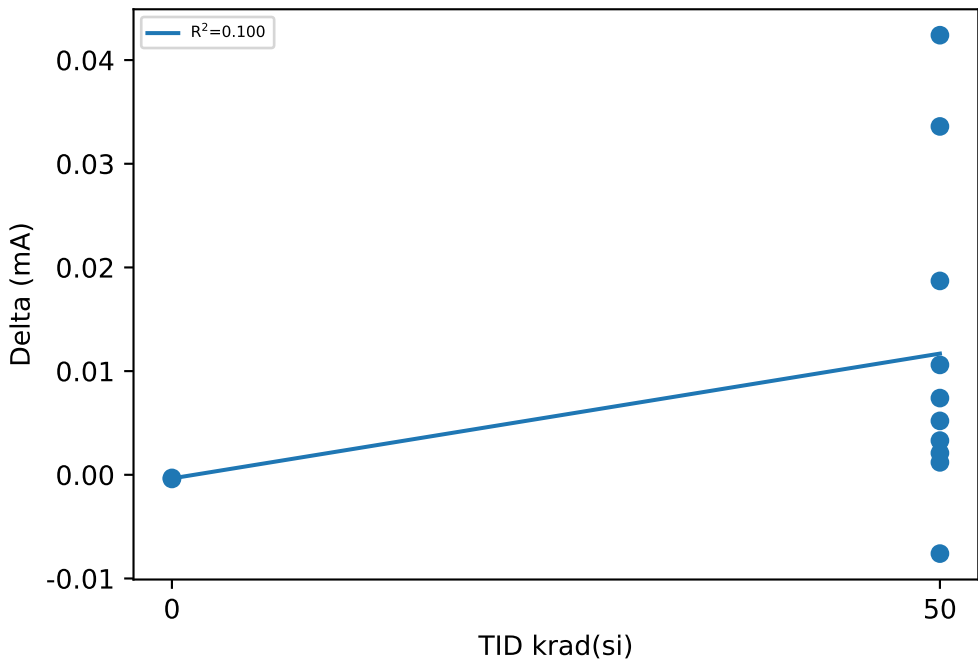
TID vs Result Stats



Test Results (Upper Limit = 5.0 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.7922	3.7918	-0.0004
2	0	Correlation	3.74	3.7397	-0.0003
4	50	Bias	3.7641	3.7747	0.0106
6	50	Bias	3.7361	3.7285	-0.0076
7	50	Bias	3.7632	3.7644	0.0012
8	50	Bias	3.778	3.7813	0.0033
9	50	Bias	3.7702	3.7776	0.0074
11	50	Unbias	3.735	3.7402	0.0052
12	50	Unbias	3.7186	3.7207	0.0021
13	50	Unbias	3.7422	3.7758	0.0336
14	50	Unbias	3.7633	3.782	0.0187
15	50	Unbias	3.8173	3.8597	0.0424

TID vs Post - Pre Exposure Delta

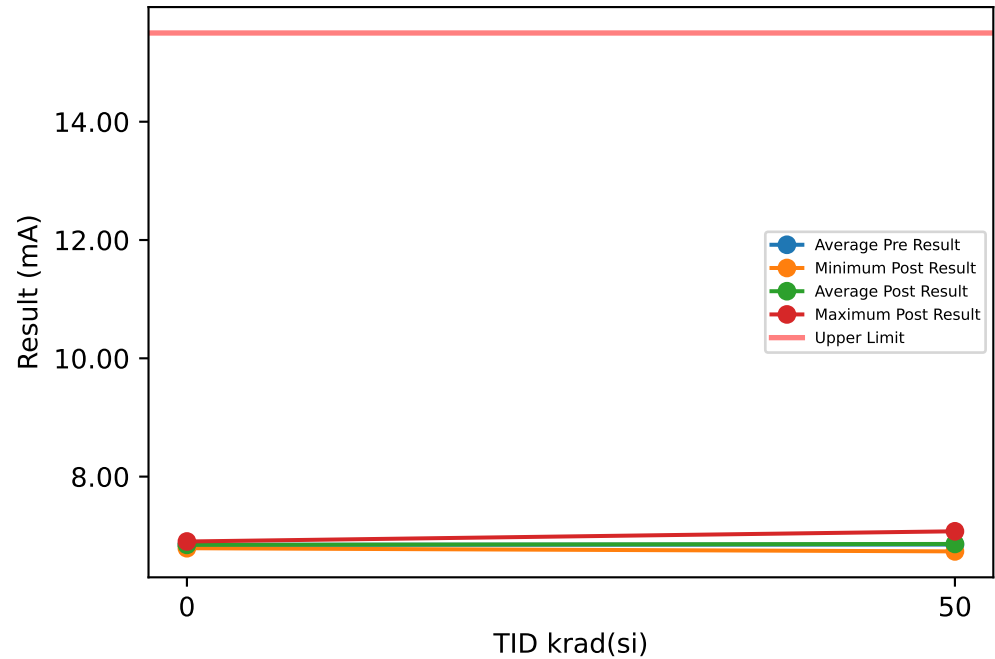


Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.74	3.7661	3.7922	0.036911	3.7397	3.7658	3.7918	0.03684	-0.0004	-0.00035	-0.0003	7.0711e-05
50	3.7186	3.7588	3.8173	0.027813	3.7207	3.7705	3.8597	0.038731	-0.0076	0.01169	0.0424	0.015558

Device Test: 14.6 IDD_ACT_500K_NOLOAD(IDD|SUPPLY CURRENT/IN/4.5/4.5/0/0/4.5/500kHz//@IDD_ACT_500K_NOLOAD

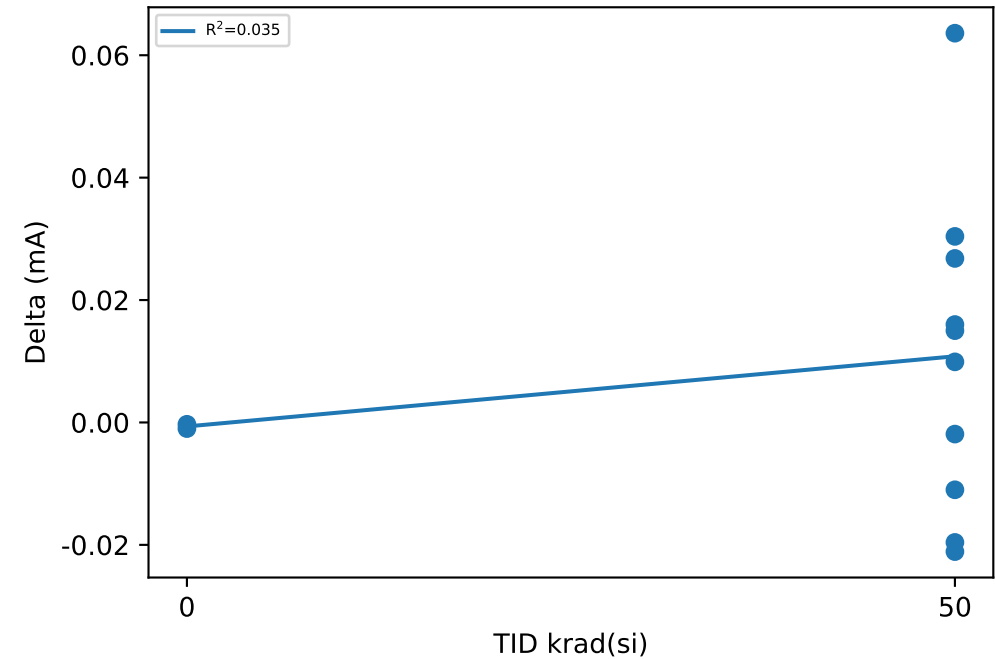
TID vs Result Stats



Test Results (Upper Limit = 15.5 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	6.9035	6.9032	-0.0003
2	0	Correlation	6.7903	6.7893	-0.001
4	50	Bias	6.8993	6.8974	-0.0019
6	50	Bias	6.8083	6.7872	-0.0211
7	50	Bias	6.8133	6.8283	0.015
8	50	Bias	6.8868	6.9028	0.016
9	50	Bias	6.8323	6.8422	0.0099
11	50	Unbias	6.819	6.8458	0.0268
12	50	Unbias	6.7552	6.7356	-0.0196
13	50	Unbias	6.8263	6.8567	0.0304
14	50	Unbias	6.8569	6.8459	-0.011
15	50	Unbias	7.0118	7.0754	0.0636

TID vs Post - Pre Exposure Delta

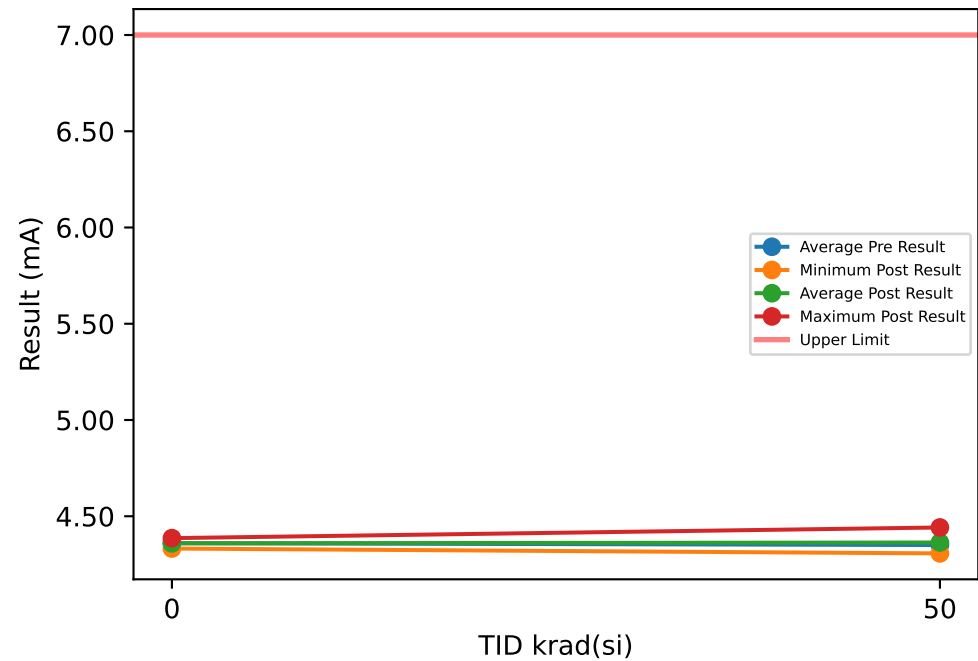


Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.7903	6.8469	6.9035	0.080044	6.7893	6.8462	6.9032	0.080539	-0.001	-0.00065	-0.0003	0.00049497
50	6.7552	6.8509	7.0118	0.069851	6.7356	6.8617	7.0754	0.089509	-0.0211	0.01081	0.0636	0.025931

Device Test: 14.7 IDD_DIS(IDD_DIS|STANDBY CURRENT/IN/4.5/4.5/0/0/4.5/500kHz//@IDD_DIS)

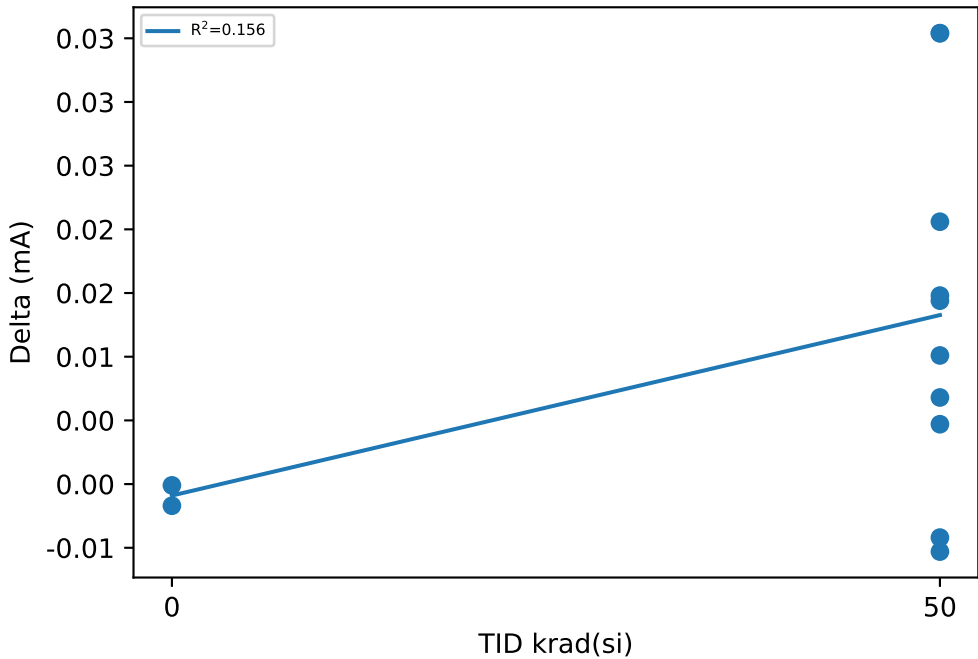
TID vs Result Stats



Test Results (Upper Limit = 7.0 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.3864	4.3863	-0.0001
2	0	Correlation	4.3339	4.3322	-0.0017
4	50	Bias	4.3586	4.3654	0.0068
6	50	Bias	4.3294	4.3252	-0.0042
7	50	Bias	4.3576	4.3623	0.0047
8	50	Bias	4.3639	4.3787	0.0148
9	50	Bias	4.3619	4.372	0.0101
11	50	Unbias	4.3178	4.3322	0.0144
12	50	Unbias	4.3123	4.307	-0.0053
13	50	Unbias	4.3397	4.3751	0.0354
14	50	Unbias	4.3564	4.377	0.0206
15	50	Unbias	4.4063	4.4417	0.0354

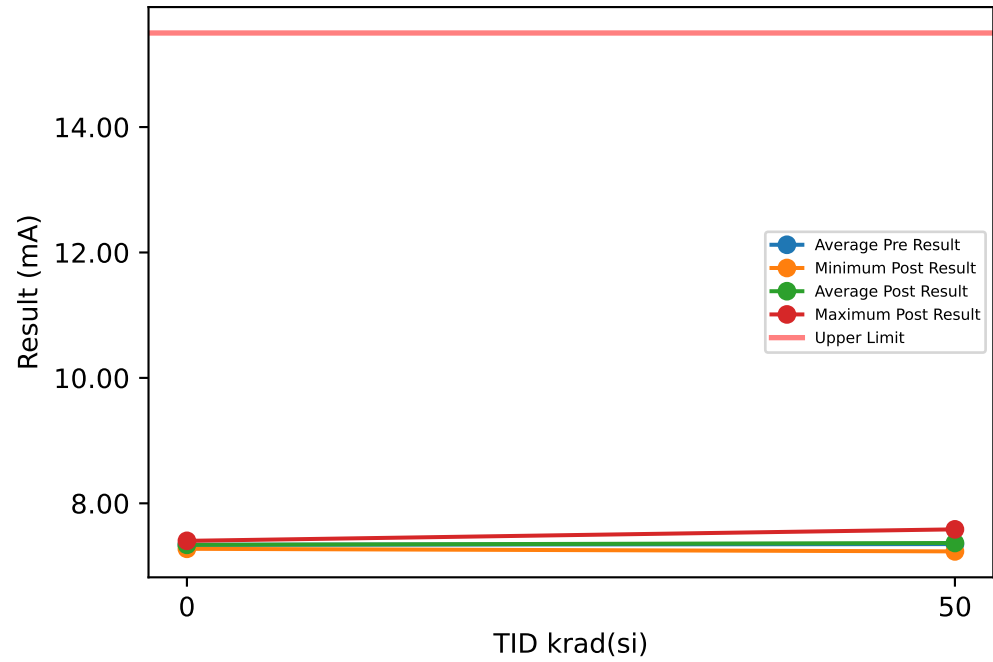
TID vs Post - Pre Exposure Delta



Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.3339	4.3601	4.3864	0.037123	4.3322	4.3592	4.3863	0.038254	-0.0017	-0.0009	-0.0001	0.0011314
50	4.3123	4.3504	4.4063	0.027212	4.307	4.3637	4.4417	0.037087	-0.0053	0.01327	0.0354	0.01419

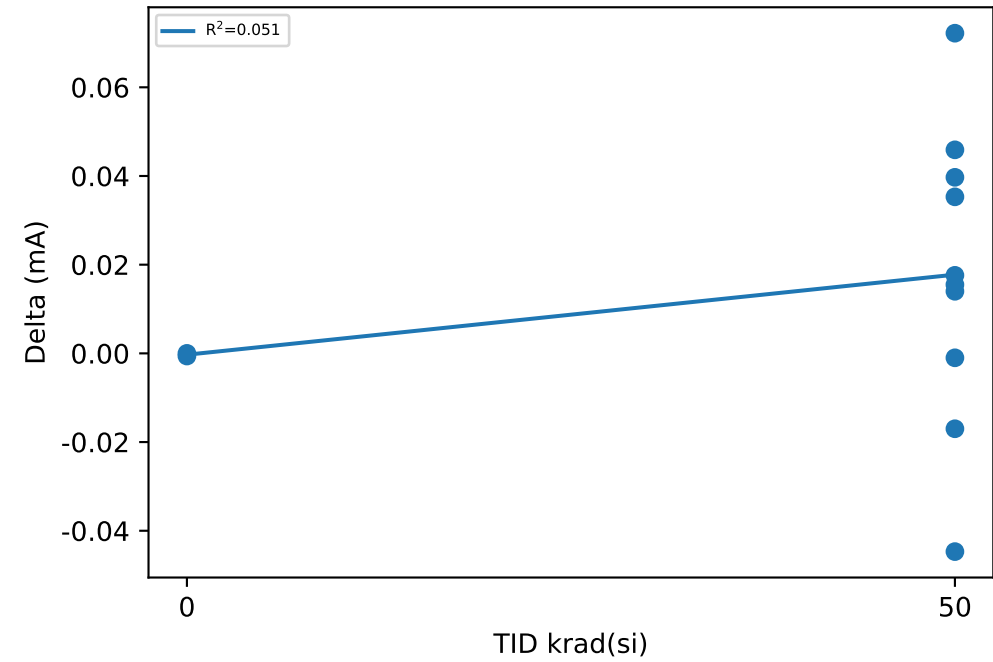
TID vs Result Stats



Test Results (Upper Limit = 15.5 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.4022	7.4016	-0.0006
2	0	Correlation	7.2746	7.2746	0
4	50	Bias	7.4017	7.4007	-0.001
6	50	Bias	7.3256	7.3086	-0.017
7	50	Bias	7.3095	7.325	0.0155
8	50	Bias	7.3854	7.403	0.0176
9	50	Bias	7.3441	7.3581	0.014
11	50	Unbias	7.3037	7.3434	0.0397
12	50	Unbias	7.278	7.2333	-0.0447
13	50	Unbias	7.3121	7.358	0.0459
14	50	Unbias	7.3257	7.361	0.0353
15	50	Unbias	7.5126	7.5848	0.0722

TID vs Post - Pre Exposure Delta

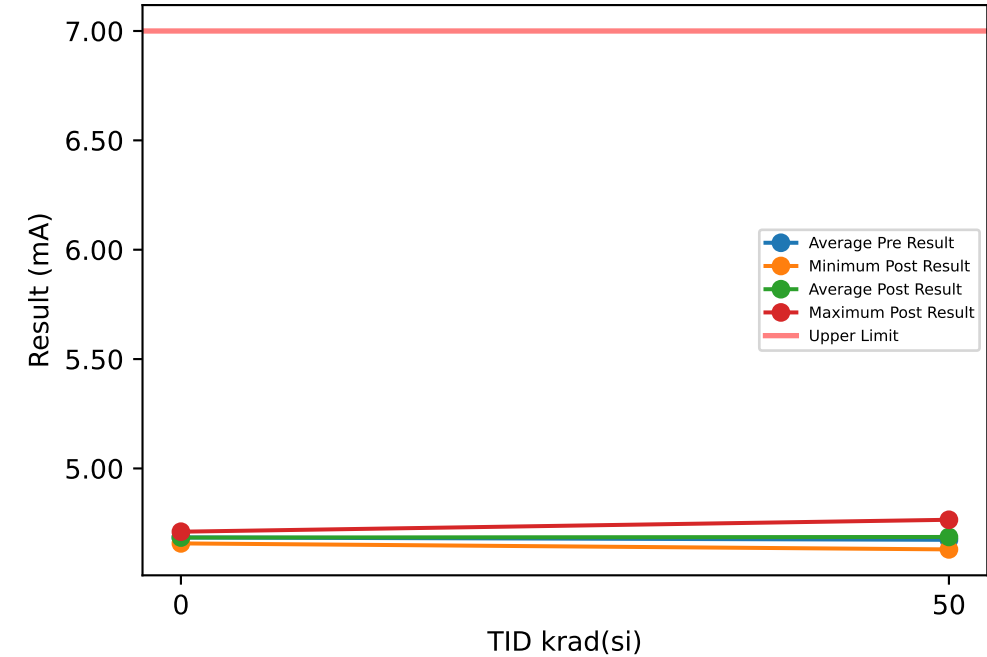


Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.2746	7.3384	7.4022	0.090227	7.2746	7.3381	7.4016	0.089803	-0.0006	-0.0003	0	0.00042426
50	7.278	7.3498	7.5126	0.068305	7.2333	7.3676	7.5848	0.090473	-0.0447	0.01775	0.0722	0.033375

Device Test: 14.9 IDD_DIS(IDD_DIS|STANDBY CURRENT/IN/5/5/0/0/5/500kHz//@IDD_DIS)

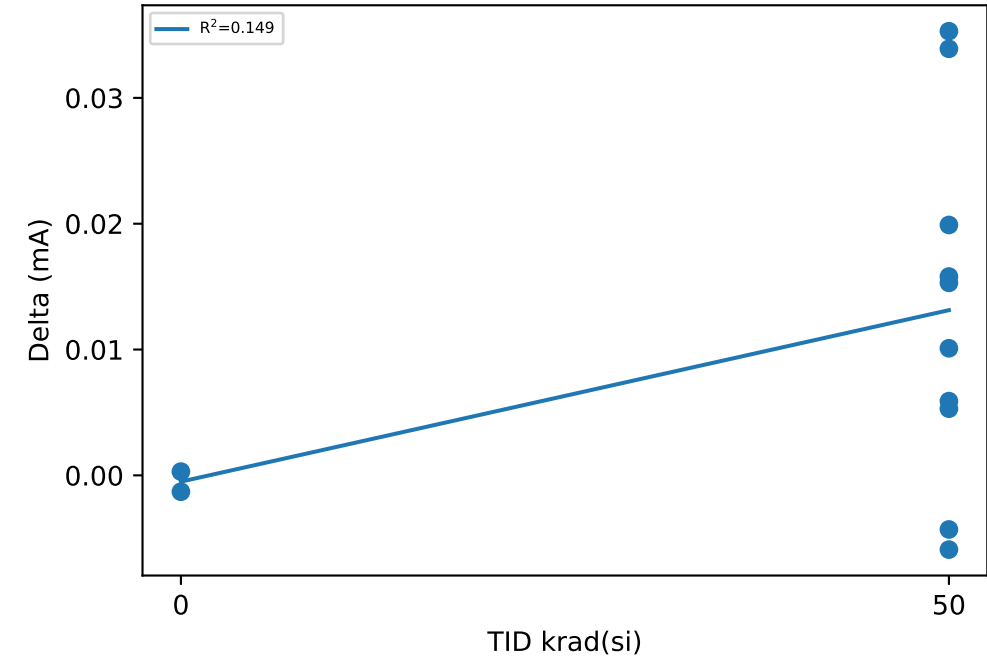
TID vs Result Stats



Test Results (Upper Limit = 7.0 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.7121	4.7108	-0.0013
2	0	Correlation	4.657	4.6573	0.0003
4	50	Bias	4.6836	4.6889	0.0053
6	50	Bias	4.6525	4.6482	-0.0043
7	50	Bias	4.6809	4.6868	0.0059
8	50	Bias	4.6858	4.7016	0.0158
9	50	Bias	4.6847	4.6948	0.0101
11	50	Unbias	4.6405	4.6558	0.0153
12	50	Unbias	4.6358	4.6299	-0.0059
13	50	Unbias	4.6633	4.6972	0.0339
14	50	Unbias	4.6791	4.699	0.0199
15	50	Unbias	4.73	4.7653	0.0353

TID vs Post - Pre Exposure Delta

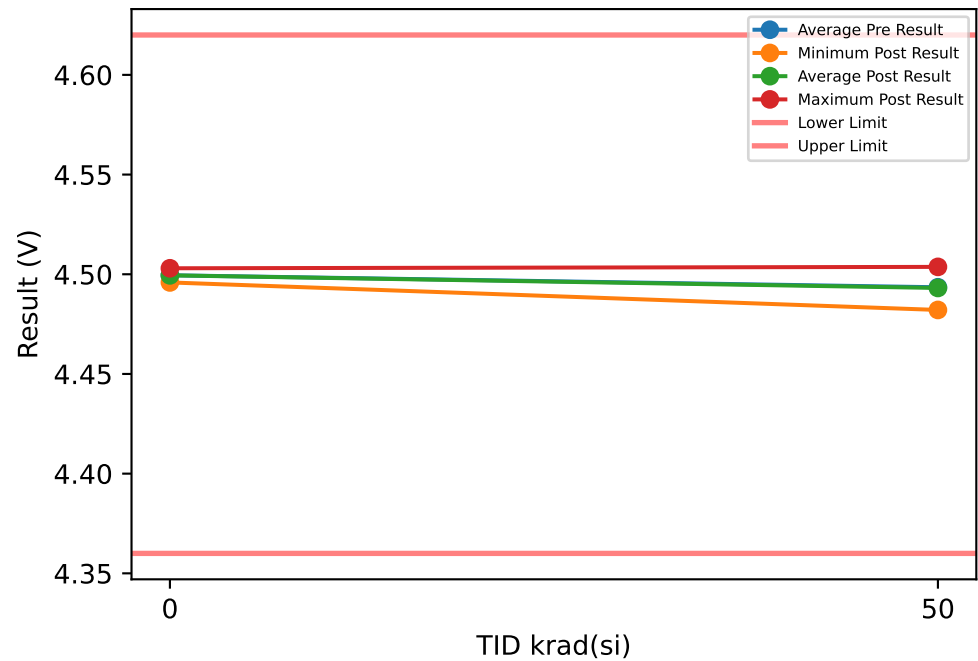


Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.657	4.6845	4.7121	0.038962	4.6573	4.684	4.7108	0.03783	-0.0013	-0.0005	0.0003	0.0011314
50	4.6358	4.6736	4.73	0.02731	4.6299	4.6867	4.7653	0.037111	-0.0059	0.01313	0.0353	0.014021

Device Test: 15.1 V_LDO_4P5(VLDO|V_VLDO/VLDO/5/5/0/0/4.5/500kHz//@V_LDO_4P5)

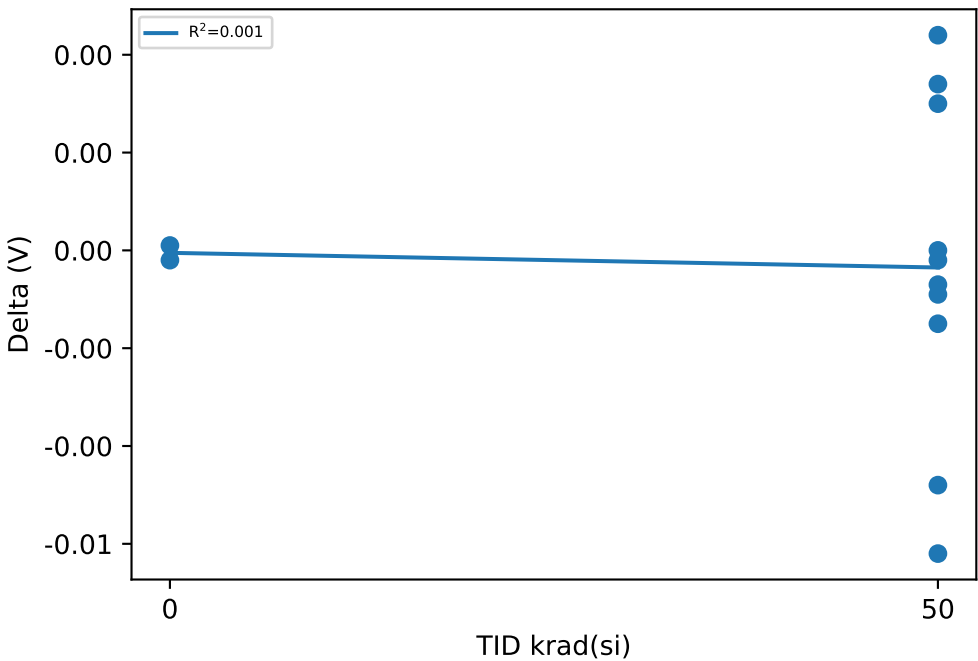
TID vs Result Stats



Test Results (Lower Limit = 4.36, Upper Limit = 4.62 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.4961	4.4959	-0.0002
2	0	Correlation	4.5029	4.503	0.0001
4	50	Bias	4.492	4.4964	0.0044
6	50	Bias	4.5052	4.5037	-0.0015
7	50	Bias	4.5001	4.4992	-0.0009
8	50	Bias	4.497	4.4922	-0.0048
9	50	Bias	4.5015	4.4953	-0.0062
11	50	Unbias	4.4851	4.4851	0
12	50	Unbias	4.4787	4.4821	0.0034
13	50	Unbias	4.4982	4.498	-0.0002
14	50	Unbias	4.4859	4.4852	-0.0007
15	50	Unbias	4.4911	4.4941	0.003

TID vs Post - Pre Exposure Delta

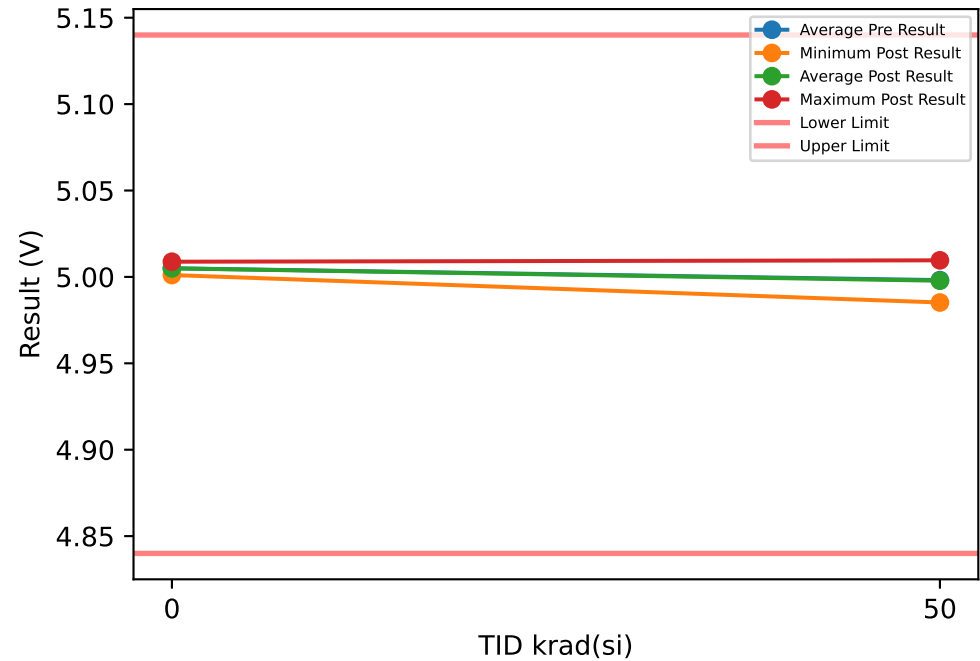


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.4961	4.4995	4.5029	0.0048083	4.4959	4.4994	4.503	0.0050205	-0.0002	-5e-05	0.0001	0.00021213
50	4.4787	4.4935	4.5052	0.0083942	4.4821	4.4931	4.5037	0.0069803	-0.0062	-0.00035	0.0044	0.0033955

Device Test: 15.11 V_LDO_5(VLDO|V_VLDO/VLDO/12/12/0/0/5/500kHz//@V_LDO_5)

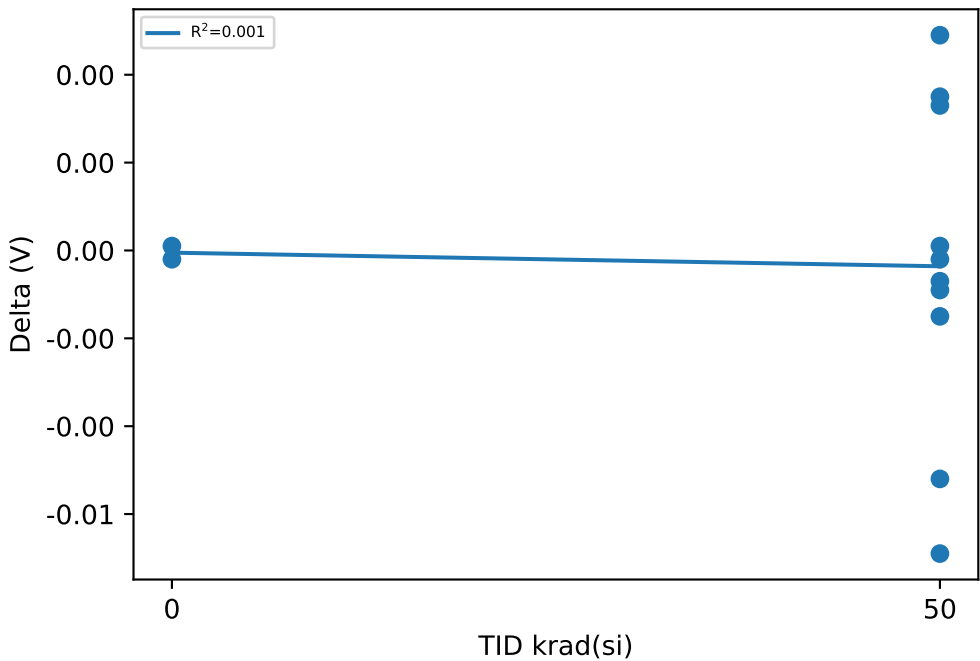
TID vs Result Stats



Test Results (Lower Limit = 4.84, Upper Limit = 5.14 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0013	5.0011	-0.0002
2	0	Correlation	5.0087	5.0088	0.0001
4	50	Bias	4.9965	5.0014	0.0049
6	50	Bias	5.0111	5.0096	-0.0015
7	50	Bias	5.0055	5.0046	-0.0009
8	50	Bias	5.0019	4.9967	-0.0052
9	50	Bias	5.0071	5.0002	-0.0069
11	50	Unbias	4.9889	4.989	0.0001
12	50	Unbias	4.9817	4.9852	0.0035
13	50	Unbias	5.0035	5.0033	-0.0002
14	50	Unbias	4.9898	4.9891	-0.0007
15	50	Unbias	4.9956	4.9989	0.0033

TID vs Post - Pre Exposure Delta

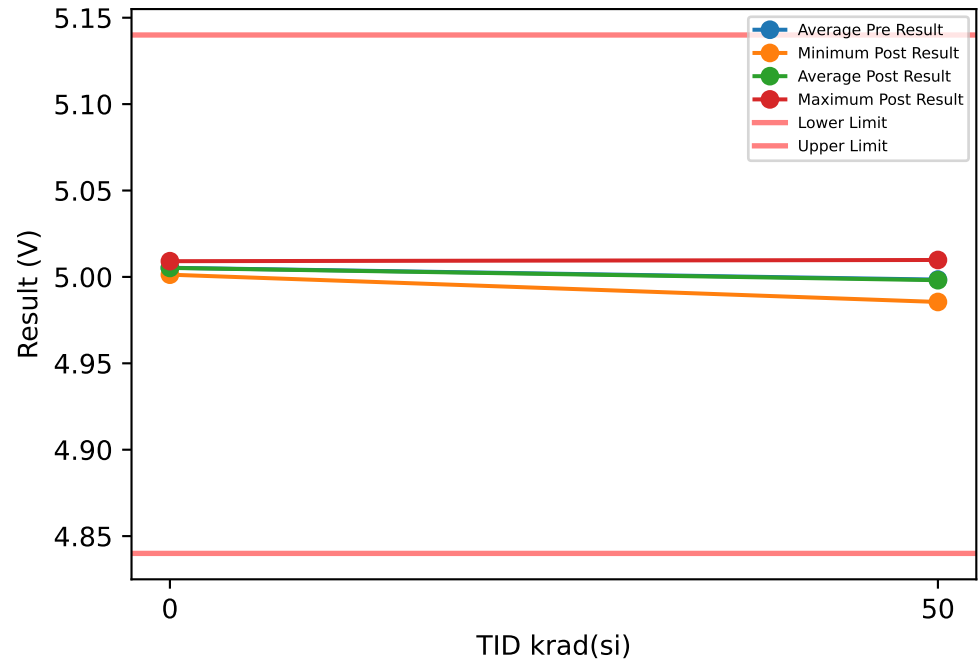


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0013	5.005	5.0087	0.0052326	5.0011	5.005	5.0088	0.0054447	-0.0002	-5e-05	0.0001	0.00021213
50	4.9817	4.9982	5.0111	0.0093072	4.9852	4.9978	5.0096	0.0078085	-0.0069	-0.00036	0.0049	0.0037134

Device Test: 15.12 V_LDO_5(VLDO|V_VLDO/VLDO/14/14/0/0/5/500kHz//@V_LDO_5)

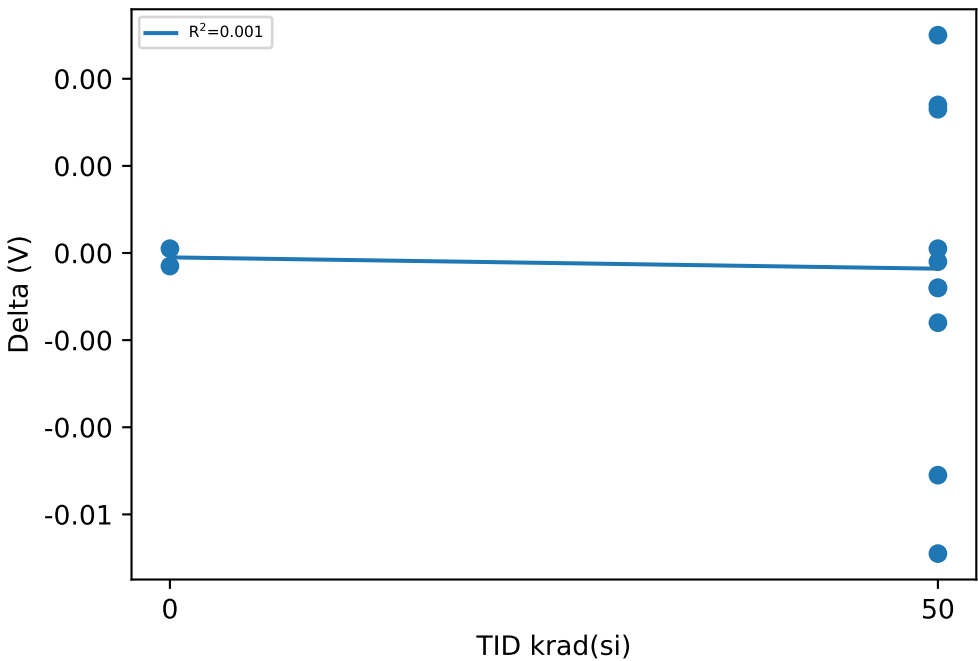
TID vs Result Stats



Test Results (Lower Limit = 4.84, Upper Limit = 5.14 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0016	5.0013	-0.0003
2	0	Correlation	5.009	5.0091	0.0001
4	50	Bias	4.9967	5.0017	0.005
6	50	Bias	5.0114	5.0098	-0.0016
7	50	Bias	5.0058	5.005	-0.0008
8	50	Bias	5.0022	4.9971	-0.0051
9	50	Bias	5.0074	5.0005	-0.0069
11	50	Unbias	4.9891	4.9892	0.0001
12	50	Unbias	4.9821	4.9855	0.0034
13	50	Unbias	5.0038	5.0036	-0.0002
14	50	Unbias	4.9902	4.9894	-0.0008
15	50	Unbias	4.9959	4.9992	0.0033

TID vs Post - Pre Exposure Delta

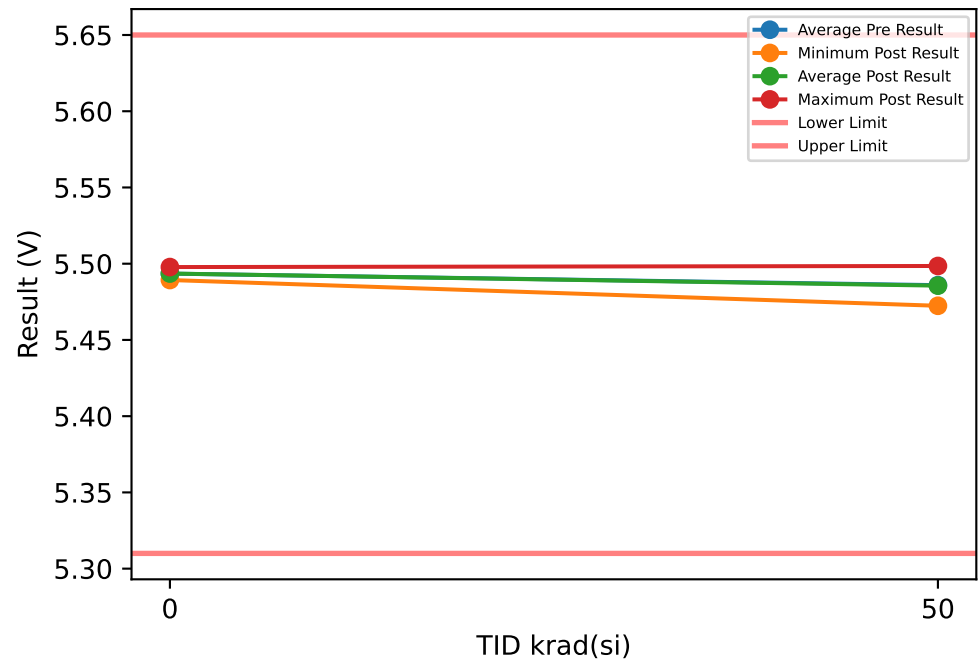


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0016	5.0053	5.009	0.0052326	5.0013	5.0052	5.0091	0.0055154	-0.0003	-0.0001	0.0001	0.00028284
50	4.9821	4.9985	5.0114	0.0092909	4.9855	4.9981	5.0098	0.0078127	-0.0069	-0.00036	0.005	0.0037068

Device Test: 15.15 V_LDO_5P5(VLDO|V_VLDO/VLDO/6/6/0/0/5.5/500kHz//@V_LDO_5P5)

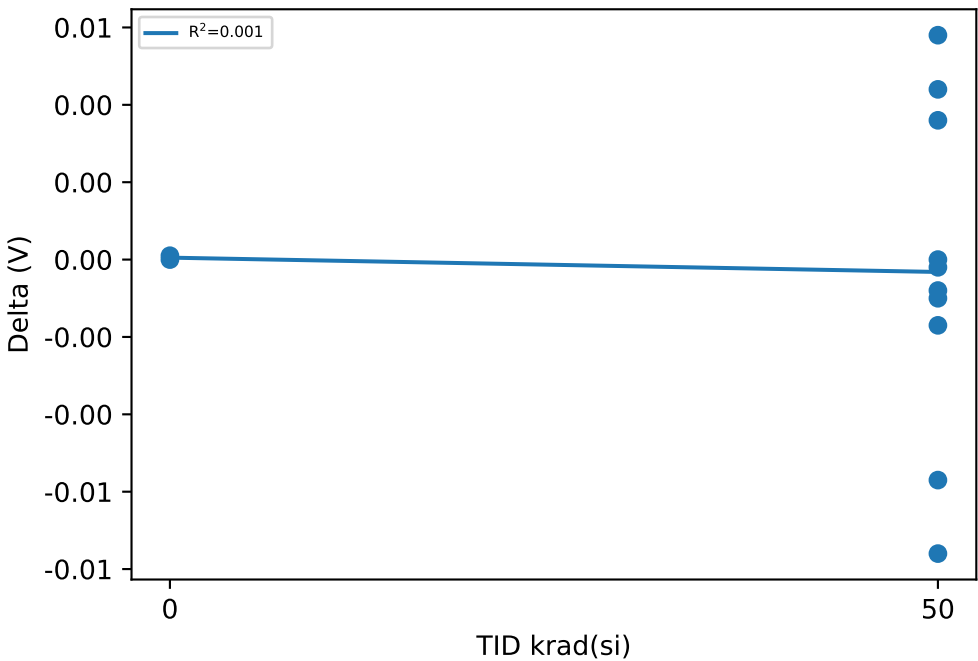
TID vs Result Stats



Test Results (Lower Limit = 5.31, Upper Limit = 5.65 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.4893	5.4893	0
2	0	Correlation	5.4977	5.4978	0.0001
4	50	Bias	5.484	5.4898	0.0058
6	50	Bias	5.5002	5.4985	-0.0017
7	50	Bias	5.494	5.493	-0.001
8	50	Bias	5.4901	5.4844	-0.0057
9	50	Bias	5.4956	5.488	-0.0076
11	50	Unbias	5.4757	5.4757	0
12	50	Unbias	5.468	5.4724	0.0044
13	50	Unbias	5.4917	5.4915	-0.0002
14	50	Unbias	5.4769	5.4761	-0.0008
15	50	Unbias	5.4831	5.4867	0.0036

TID vs Post - Pre Exposure Delta

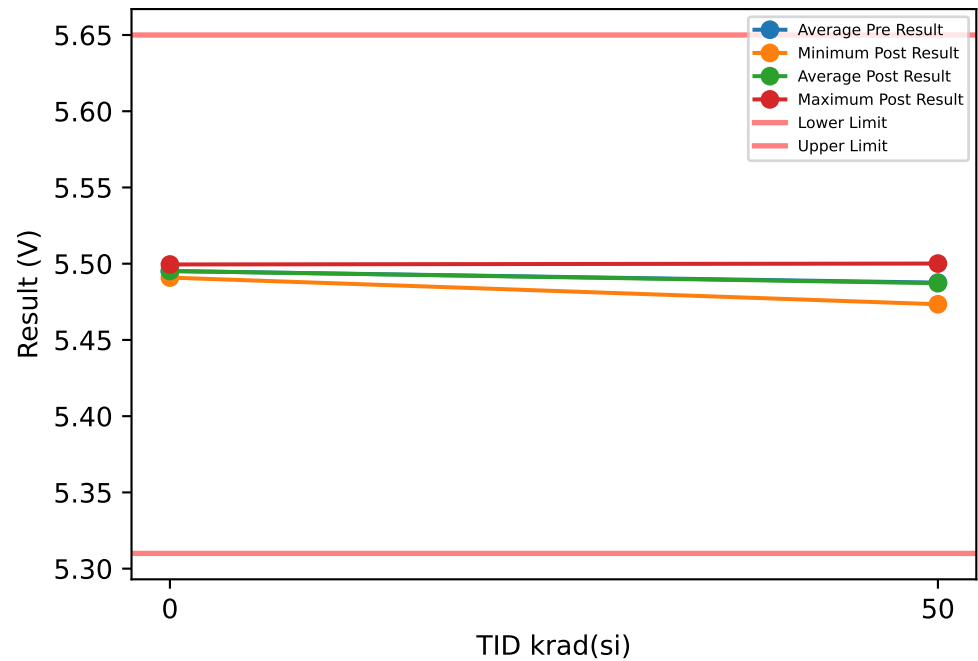


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4893	5.4935	5.4977	0.0059397	5.4893	5.4935	5.4978	0.0060104	0	5e-05	0.0001	7.0711e-05
50	5.468	5.4859	5.5002	0.010178	5.4724	5.4856	5.4985	0.0084625	-0.0076	-0.00032	0.0058	0.0042132

Device Test: 15.18 V_LDO_5P5(VLDO|V_VLDO/VLDO/12/12/0/0/5.5/500kHz//@V_LDO_5P5)

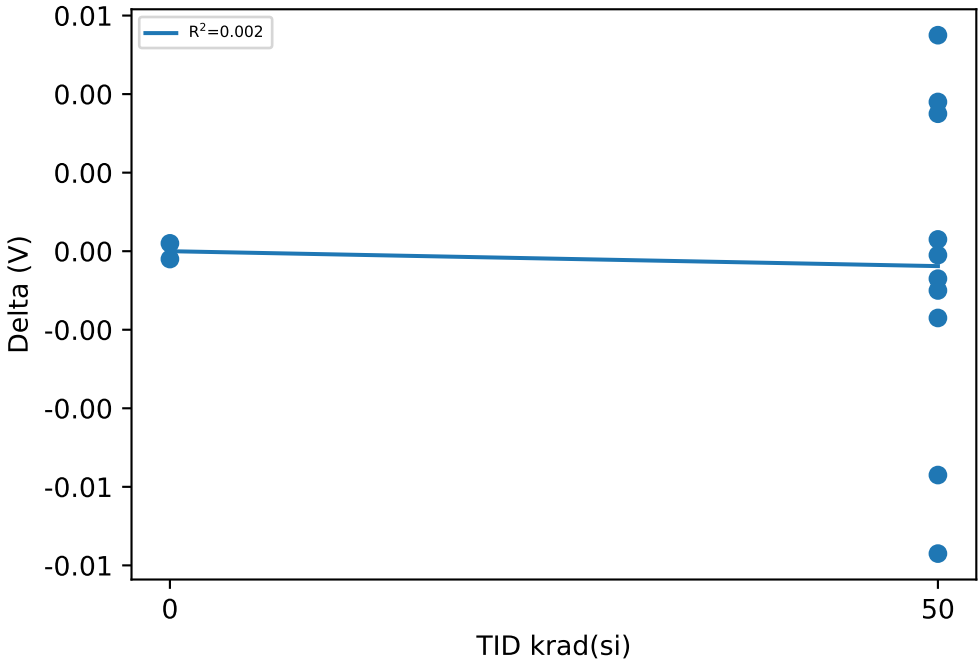
TID vs Result Stats



Test Results (Lower Limit = 5.31, Upper Limit = 5.65 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.4911	5.4909	-0.0002
2	0	Correlation	5.4993	5.4995	0.0002
4	50	Bias	5.4856	5.4911	0.0055
6	50	Bias	5.5018	5.5001	-0.0017
7	50	Bias	5.4957	5.4947	-0.001
8	50	Bias	5.4917	5.486	-0.0057
9	50	Bias	5.4975	5.4898	-0.0077
11	50	Unbias	5.4774	5.4777	0.0003
12	50	Unbias	5.4696	5.4734	0.0038
13	50	Unbias	5.4934	5.4933	-0.0001
14	50	Unbias	5.4785	5.4778	-0.0007
15	50	Unbias	5.4848	5.4883	0.0035

TID vs Post - Pre Exposure Delta

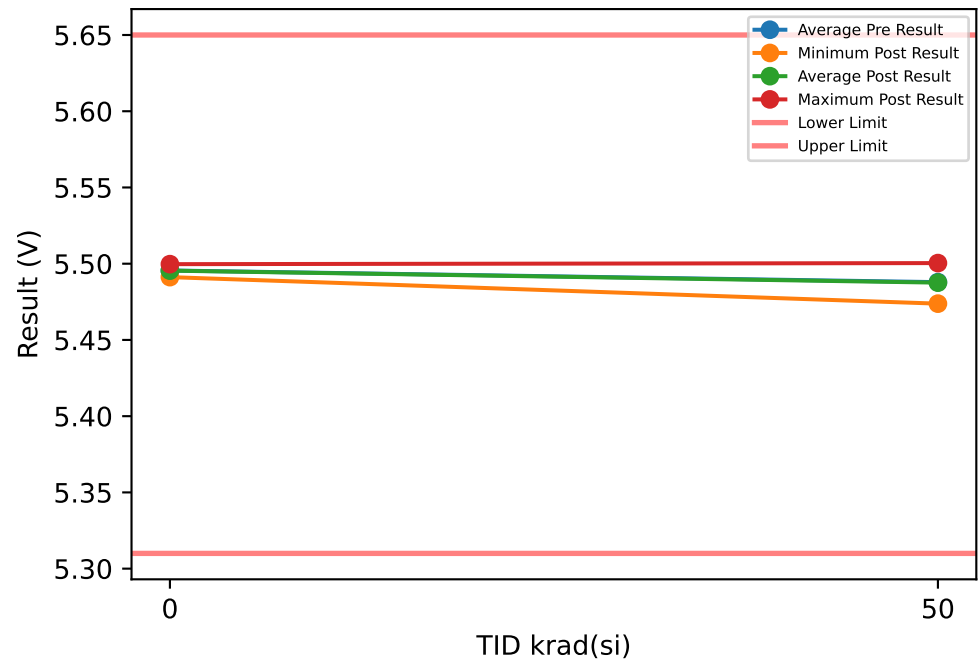


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4911	5.4952	5.4993	0.0057983	5.4909	5.4952	5.4995	0.0060811	-0.0002	0	0.0002	0.00028284
50	5.4696	5.4876	5.5018	0.010211	5.4734	5.4872	5.5001	0.0085215	-0.0077	-0.00038	0.0055	0.0041063

Device Test: 15.19 V_LDO_5P5(VLDO|V_VLDO/VLDO/14/14/0/0/5.5/500kHz//@V_LDO_5P5)

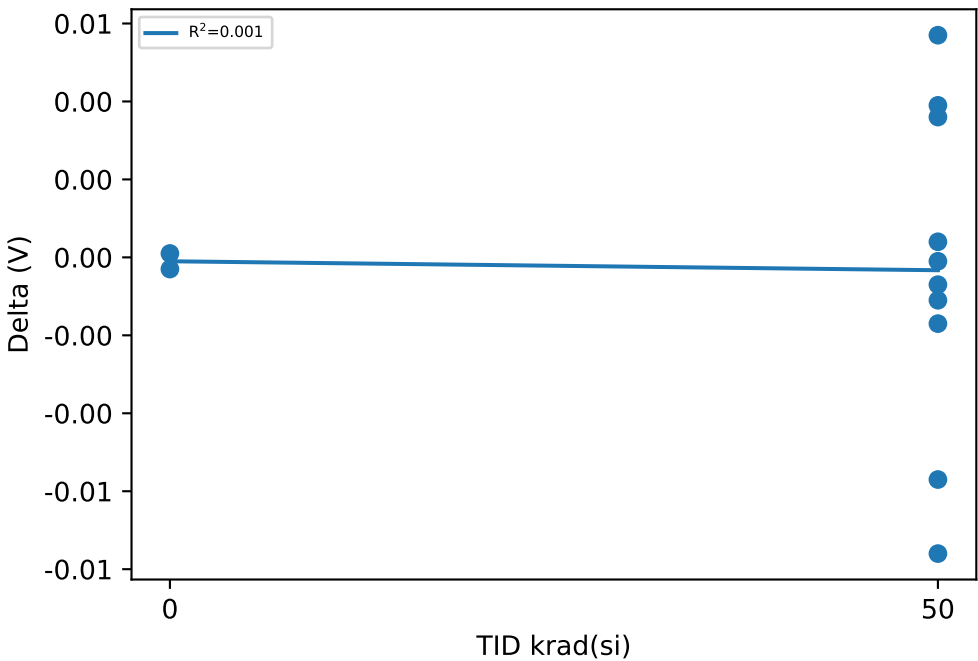
TID vs Result Stats



Test Results (Lower Limit = 5.31, Upper Limit = 5.65 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.4915	5.4912	-0.0003
2	0	Correlation	5.4996	5.4997	0.0001
4	50	Bias	5.4859	5.4916	0.0057
6	50	Bias	5.5021	5.5004	-0.0017
7	50	Bias	5.496	5.4949	-0.0011
8	50	Bias	5.4921	5.4864	-0.0057
9	50	Bias	5.4978	5.4902	-0.0076
11	50	Unbias	5.4776	5.478	0.0004
12	50	Unbias	5.4699	5.4738	0.0039
13	50	Unbias	5.4937	5.4936	-0.0001
14	50	Unbias	5.4789	5.4782	-0.0007
15	50	Unbias	5.4851	5.4887	0.0036

TID vs Post - Pre Exposure Delta

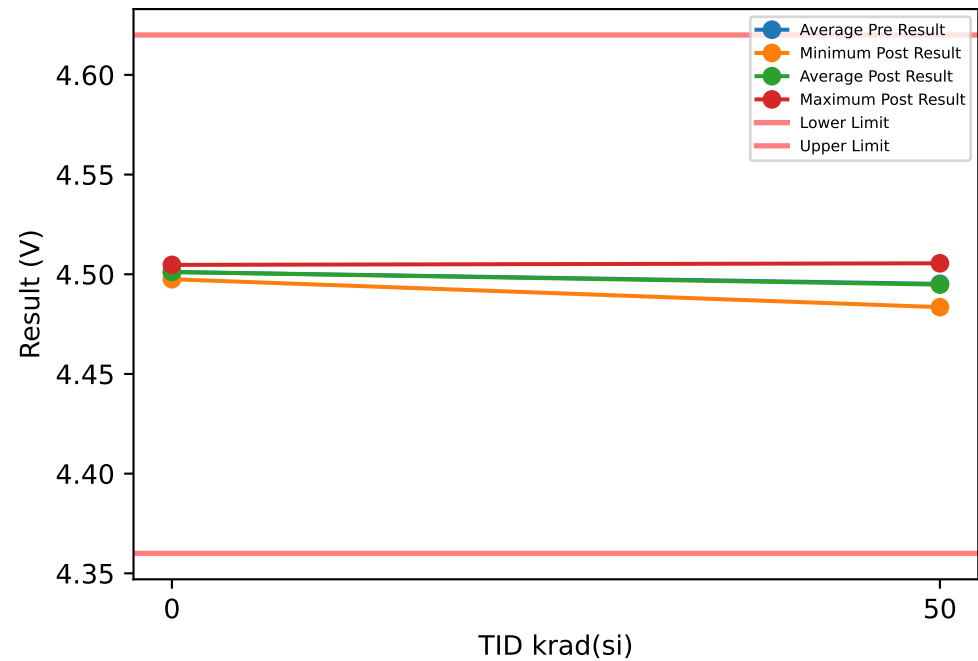


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4915	5.4955	5.4996	0.0057276	5.4912	5.4954	5.4997	0.0060104	-0.0003	-0.0001	0.0001	0.00028284
50	5.4699	5.4879	5.5021	0.010217	5.4738	5.4876	5.5004	0.0084951	-0.0076	-0.00033	0.0057	0.0041444

Device Test: 15.4 V_LDO_4P5(VLDO|V_VLDO/VLDO/12/12/0/0/4.5/500kHz//@V_LDO_4P5)

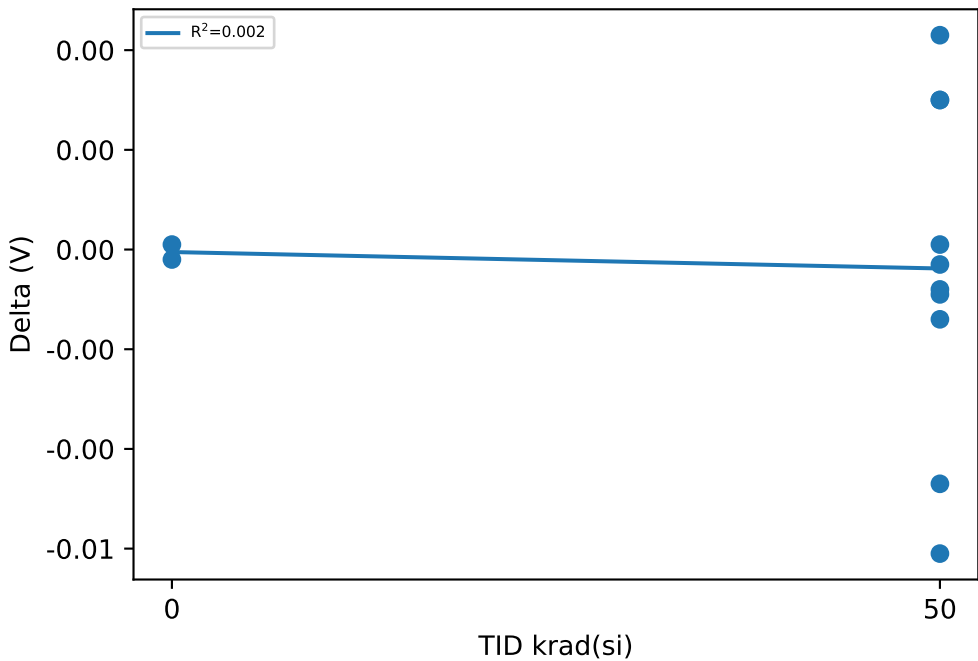
TID vs Result Stats



Test Results (Lower Limit = 4.36, Upper Limit = 4.62 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.4977	4.4975	-0.0002
2	0	Correlation	4.5046	4.5047	0.0001
4	50	Bias	4.4936	4.4979	0.0043
6	50	Bias	4.5069	4.5055	-0.0014
7	50	Bias	4.5018	4.5009	-0.0009
8	50	Bias	4.4986	4.4939	-0.0047
9	50	Bias	4.5032	4.4971	-0.0061
11	50	Unbias	4.4868	4.4869	0.0001
12	50	Unbias	4.4805	4.4835	0.003
13	50	Unbias	4.5	4.4997	-0.0003
14	50	Unbias	4.4876	4.4868	-0.0008
15	50	Unbias	4.4928	4.4958	0.003

TID vs Post - Pre Exposure Delta

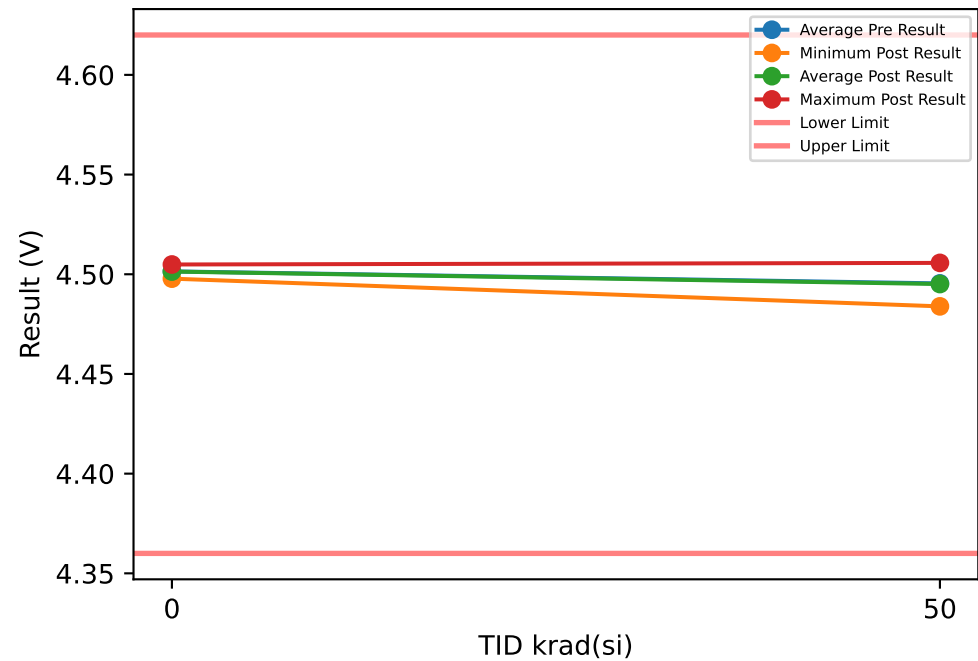


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.4977	4.5011	4.5046	0.004879	4.4975	4.5011	4.5047	0.0050912	-0.0002	-5e-05	0.0001	0.00021213
50	4.4805	4.4952	4.5069	0.0083784	4.4835	4.4948	4.5055	0.0070437	-0.0061	-0.00038	0.0043	0.0032974

Device Test: 15.5 V_LDO_4P5(VLDO|V_VLDO/VLDO/14/14/0/0/4.5/500kHz//@V_LDO_4P5)

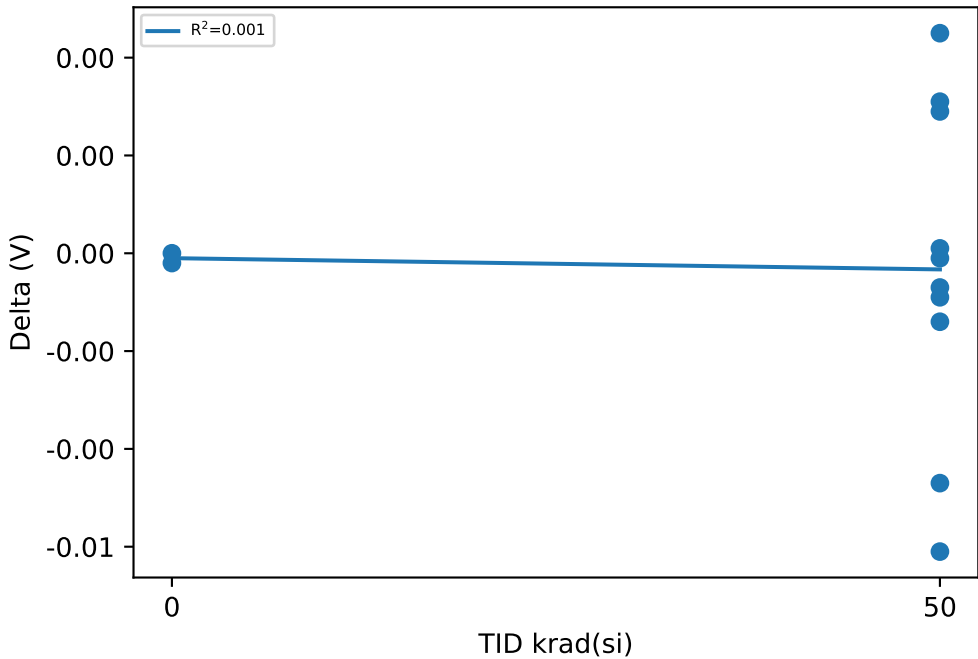
TID vs Result Stats



Test Results (Lower Limit = 4.36, Upper Limit = 4.62 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.498	4.4978	-0.0002
2	0	Correlation	4.5049	4.5049	0
4	50	Bias	4.4938	4.4983	0.0045
6	50	Bias	4.5071	4.5057	-0.0014
7	50	Bias	4.502	4.5013	-0.0007
8	50	Bias	4.4989	4.4942	-0.0047
9	50	Bias	4.5034	4.4973	-0.0061
11	50	Unbias	4.487	4.4871	0.0001
12	50	Unbias	4.4808	4.4839	0.0031
13	50	Unbias	4.5002	4.5001	-0.0001
14	50	Unbias	4.4879	4.487	-0.0009
15	50	Unbias	4.4931	4.496	0.0029

TID vs Post - Pre Exposure Delta

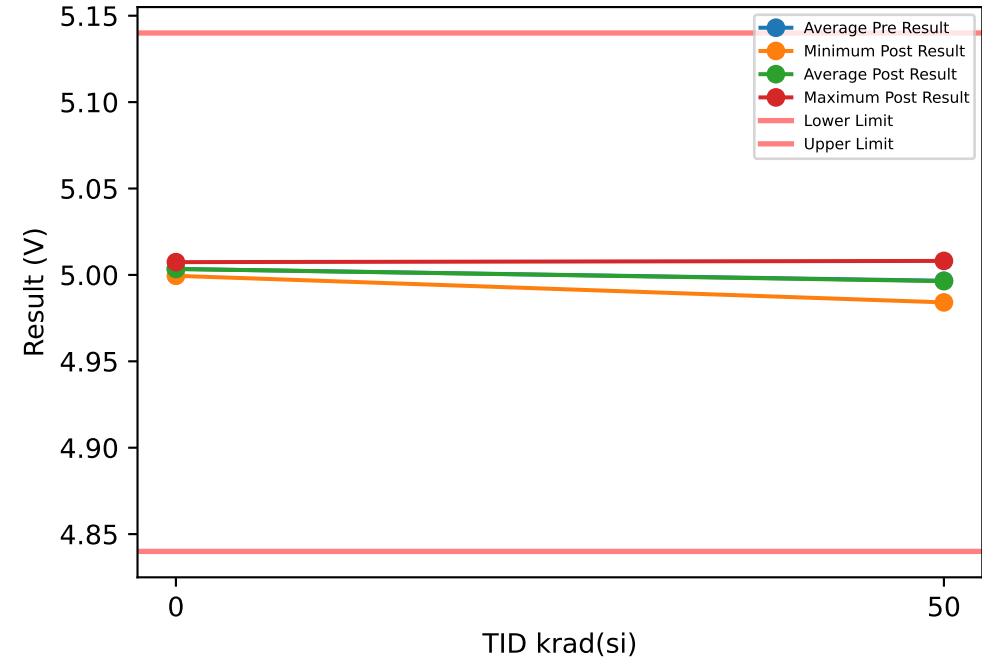


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.498	4.5015	4.5049	0.004879	4.4978	4.5014	4.5049	0.0050205	-0.0002	-0.0001	0	0.00014142
50	4.4808	4.4954	4.5071	0.0083504	4.4839	4.4951	4.5057	0.0070518	-0.0061	-0.00033	0.0045	0.0033293

Device Test: 15.8 V_LDO_5(VLDO|V_VLDO/VLDO/5.5/5.5/0/0/5/500kHz//@V_LDO_5)

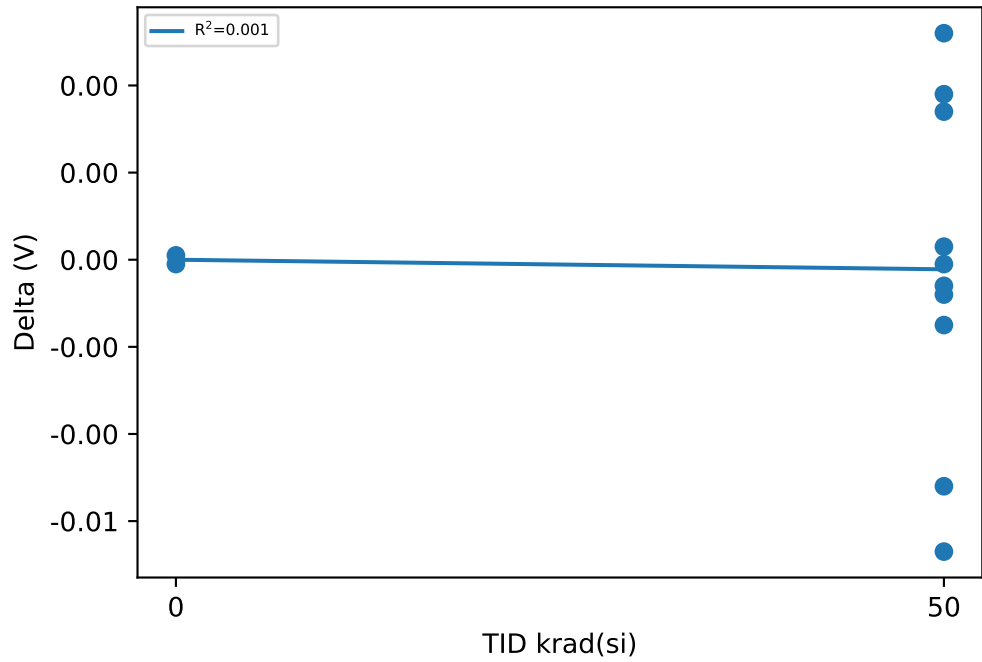
TID vs Result Stats



Test Results (Lower Limit = 4.84, Upper Limit = 5.14 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.9996	4.9995	-0.0001
2	0	Correlation	5.0073	5.0074	0.0001
4	50	Bias	4.9949	5.0001	0.0052
6	50	Bias	5.0096	5.0081	-0.0015
7	50	Bias	5.0039	5.0031	-0.0008
8	50	Bias	5.0005	4.9953	-0.0052
9	50	Bias	5.0055	4.9988	-0.0067
11	50	Unbias	4.9873	4.9876	0.0003
12	50	Unbias	4.9803	4.9841	0.0038
13	50	Unbias	5.0019	5.0018	-0.0001
14	50	Unbias	4.9882	4.9876	-0.0006
15	50	Unbias	4.9941	4.9975	0.0034

TID vs Post - Pre Exposure Delta

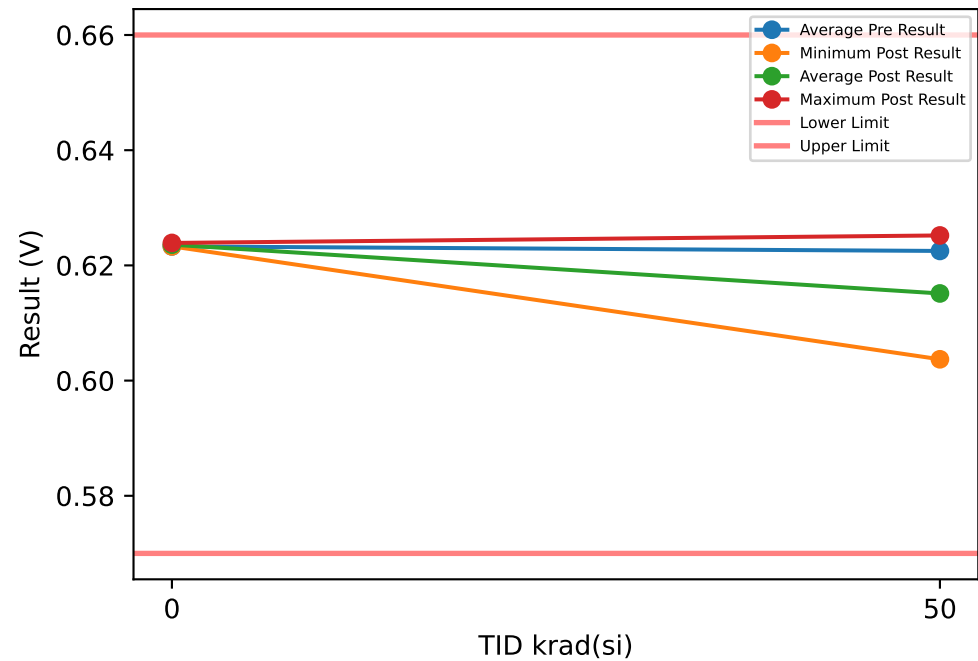


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9996	5.0034	5.0073	0.0054447	4.9995	5.0034	5.0074	0.0055861	-0.0001	0	0.0001	0.00014142
50	4.9803	4.9966	5.0096	0.0092896	4.9841	4.9964	5.0081	0.0077386	-0.0067	-0.00022	0.0052	0.0037688

Device Test: 16.1 V_EN_RISE(LEVEL|EN_RISE/EN/4.5/4.5/0/0/4.5/500kHz//@V_EN_RISE)

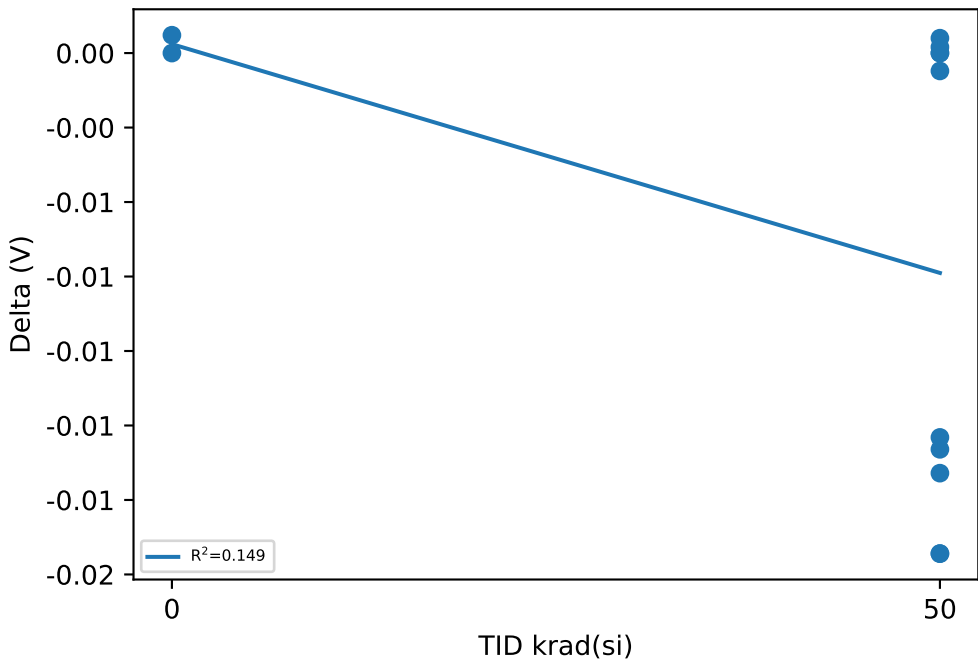
TID vs Result Stats



Test Results (Lower Limit = 0.57, Upper Limit = 0.66 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.6233	0.6239	0.0006
2	0	Correlation	0.6233	0.6233	0
4	50	Bias	0.6178	0.6037	-0.0141
6	50	Bias	0.6224	0.6056	-0.0168
7	50	Bias	0.6225	0.6092	-0.0133
8	50	Bias	0.6212	0.6083	-0.0129
9	50	Bias	0.6225	0.6057	-0.0168
11	50	Unbias	0.621	0.6212	0.0002
12	50	Unbias	0.6245	0.6245	0
13	50	Unbias	0.6247	0.6247	0
14	50	Unbias	0.6238	0.6232	-0.0006
15	50	Unbias	0.6247	0.6252	0.0005

TID vs Post - Pre Exposure Delta

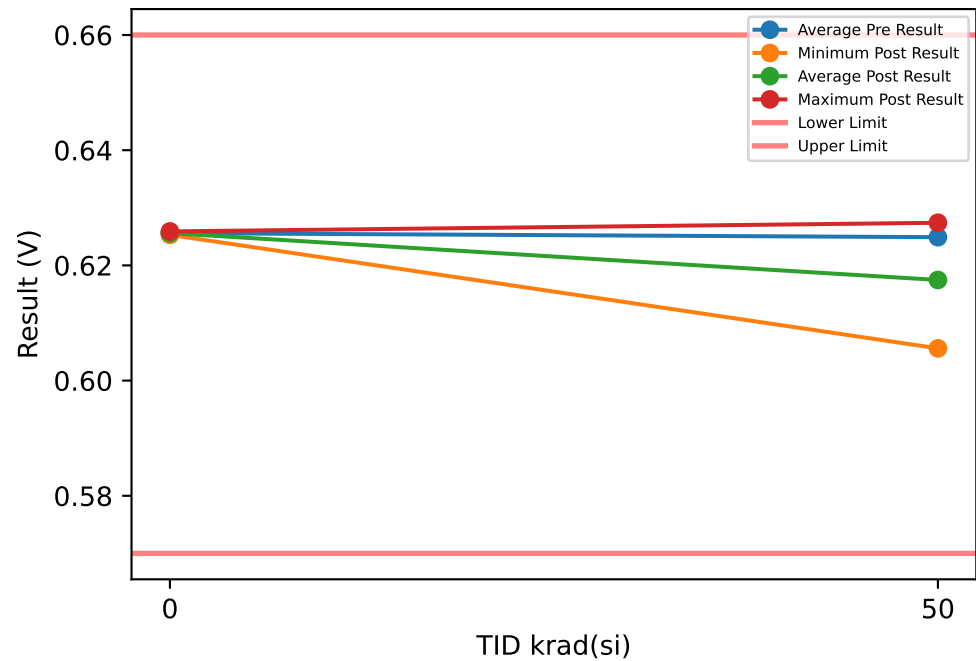


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6233	0.6233	0.6233	0	0.6233	0.6236	0.6239	0.00042426	0	0.0003	0.0006	0.00042426
50	0.6178	0.62251	0.6247	0.002145	0.6037	0.61513	0.6252	0.0092794	-0.0168	-0.00738	0.0005	0.0079064

Device Test: 16.10 V_EN_RISE(LEVEL|EN_RISE/EN/14/14/0/0/5/500kHz//@V_EN_RISE)

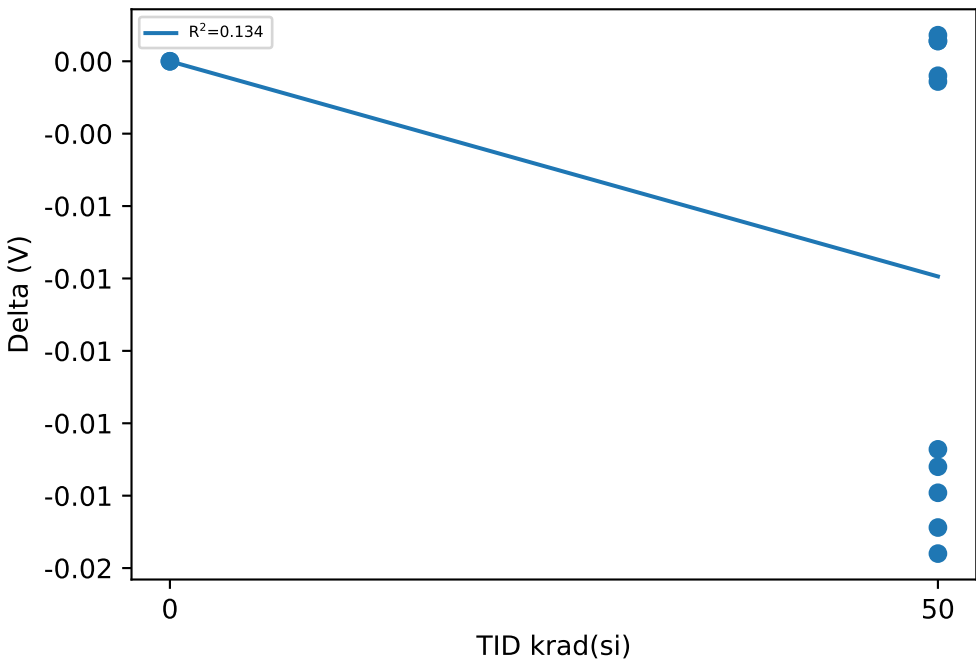
TID vs Result Stats



Test Results (Lower Limit = 0.57, Upper Limit = 0.66 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.6259	0.6259	0
2	0	Correlation	0.6253	0.6253	0
4	50	Bias	0.6205	0.6056	-0.0149
6	50	Bias	0.6245	0.6084	-0.0161
7	50	Bias	0.6252	0.6112	-0.014
8	50	Bias	0.6238	0.6104	-0.0134
9	50	Bias	0.6253	0.6083	-0.017
11	50	Unbias	0.6238	0.6233	-0.0005
12	50	Unbias	0.6265	0.6274	0.0009
13	50	Unbias	0.6267	0.6274	0.0007
14	50	Unbias	0.626	0.6253	-0.0007
15	50	Unbias	0.6267	0.6274	0.0007

TID vs Post - Pre Exposure Delta

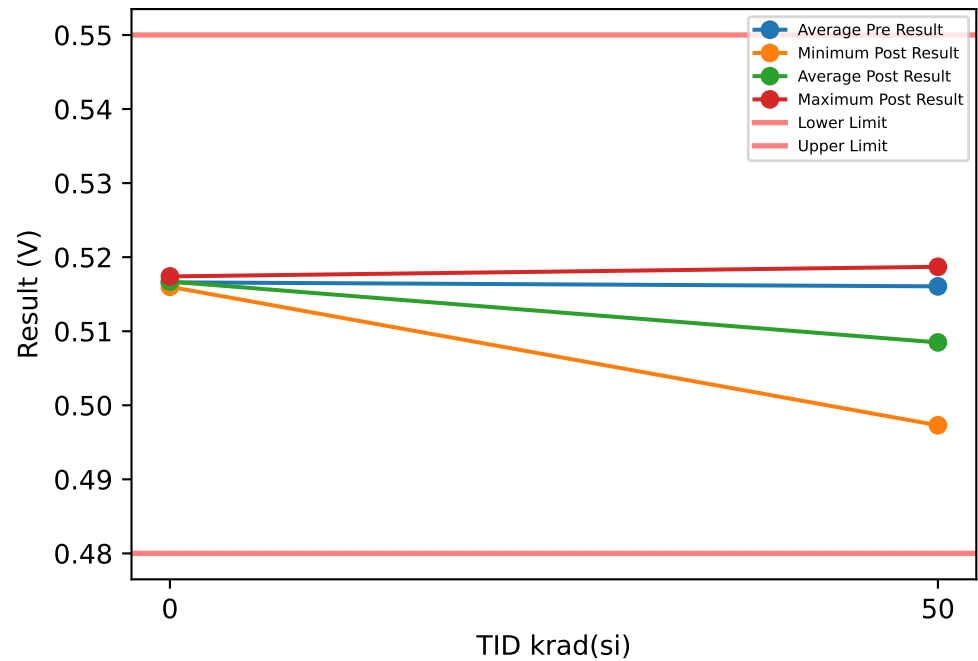


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6253	0.6256	0.6259	0.00042426	0.6253	0.6256	0.6259	0.00042426	0	0	0	0
50	0.6205	0.6249	0.6267	0.0018985	0.6056	0.61747	0.6274	0.0093551	-0.017	-0.00743	0.0009	0.0081395

Device Test: 16.11 V_EN_FALL(LEVEL|EN_FALL/EN/14/14/0/0/5/500kHz//@V_EN_FALL)

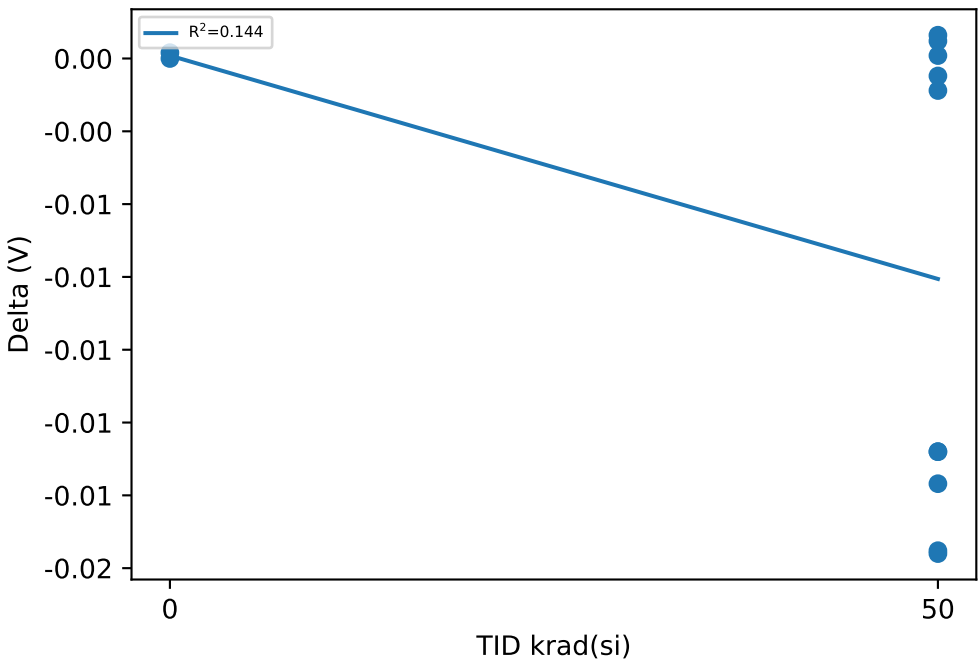
TID vs Result Stats



Test Results (Lower Limit = 0.48, Upper Limit = 0.55 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5172	0.5174	0.0002
2	0	Correlation	0.516	0.516	0
4	50	Bias	0.5119	0.4973	-0.0146
6	50	Bias	0.516	0.499	-0.017
7	50	Bias	0.5161	0.5026	-0.0135
8	50	Bias	0.5154	0.5019	-0.0135
9	50	Bias	0.516	0.4991	-0.0169
11	50	Unbias	0.5146	0.514	-0.0006
12	50	Unbias	0.5174	0.5182	0.0008
13	50	Unbias	0.5181	0.5182	0.0001
14	50	Unbias	0.517	0.5159	-0.0011
15	50	Unbias	0.5181	0.5187	0.0006

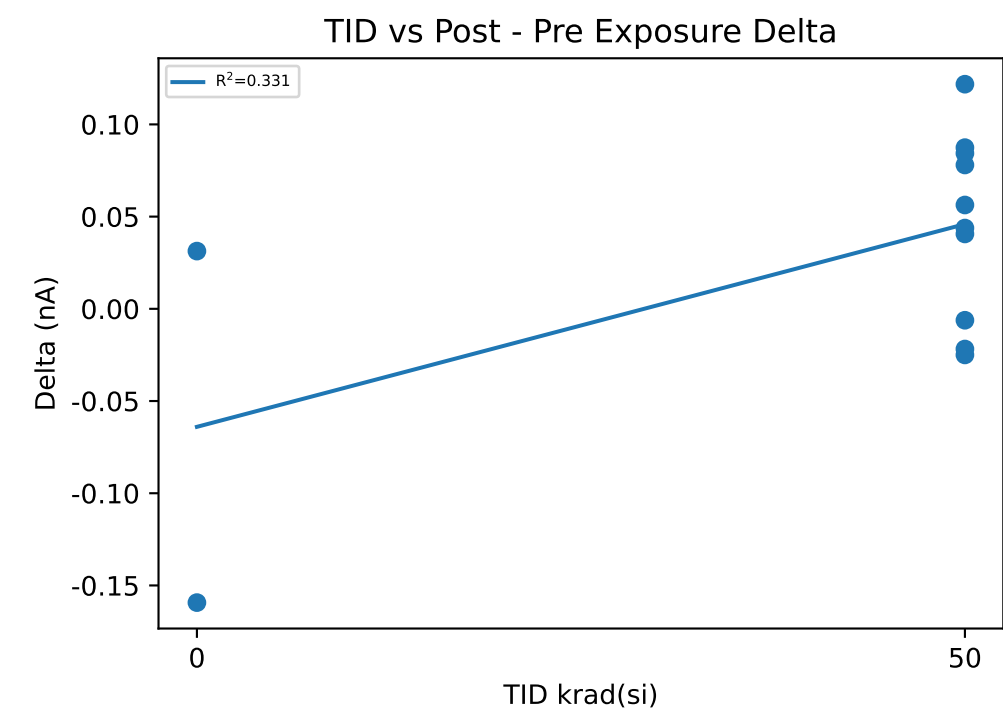
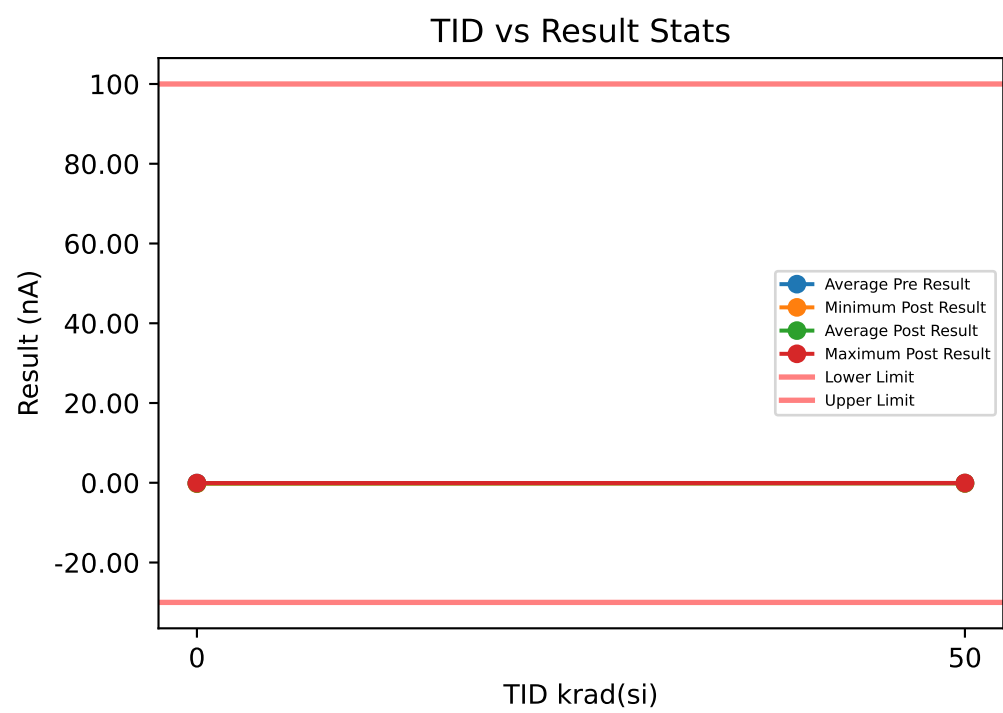
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.516	0.5166	0.5172	0.00084853	0.516	0.5167	0.5174	0.00098995	0	0.0001	0.0002	0.00014142
50	0.5119	0.51606	0.5181	0.0018524	0.4973	0.50849	0.5187	0.0091872	-0.017	-0.00757	0.0008	0.0080402

Device Test: 16.15 I_EN_LEAK_1V(LEAK|EN_LEAK/EN/14/14/0/0/5/500kHz//@I_EN_LEAK_1V)



Test Results (Lower Limit = -30.0, Upper Limit = 100.0 (nA))

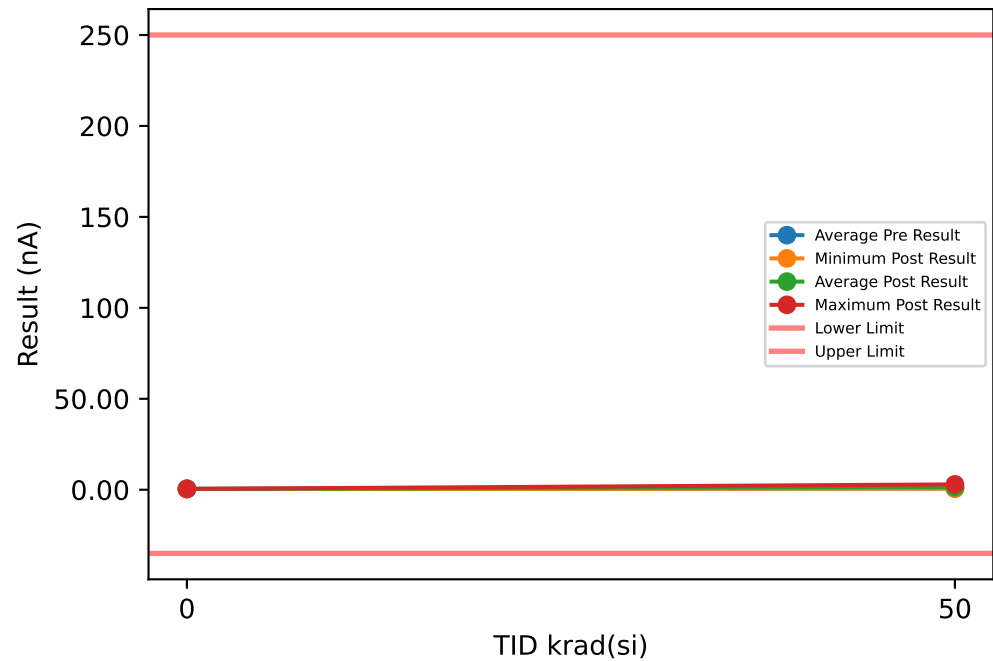
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	-0.0802	-0.2395	-0.1593
2	0	Correlation	-0.1021	-0.0708	0.0313
4	50	Bias	-0.1395	-0.0521	0.0874
6	50	Bias	-0.1333	-0.0927	0.0406
7	50	Bias	-0.0708	-0.0958	-0.025
8	50	Bias	-0.1021	-0.1083	-0.0062
9	50	Bias	-0.1833	-0.127	0.0563
11	50	Unbias	-0.152	-0.074	0.078
12	50	Unbias	-0.1302	-0.0459	0.0843
13	50	Unbias	-0.1146	-0.0708	0.0438
14	50	Unbias	-0.1458	-0.1676	-0.0218
15	50	Unbias	-0.177	-0.0552	0.1218

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.1021	-0.09115	-0.0802	0.015486	-0.2395	-0.15515	-0.0708	0.11929	-0.1593	-0.064	0.0313	0.13477
50	-0.1833	-0.13486	-0.0708	0.033613	-0.1676	-0.08894	-0.0459	0.037965	-0.025	0.04592	0.1218	0.049948

Device Test: 16.16 I_EN_LEAK(LEAK|EN_LEAK/EN/14/14/0/0/5/500kHz//@I_EN_LEAK)

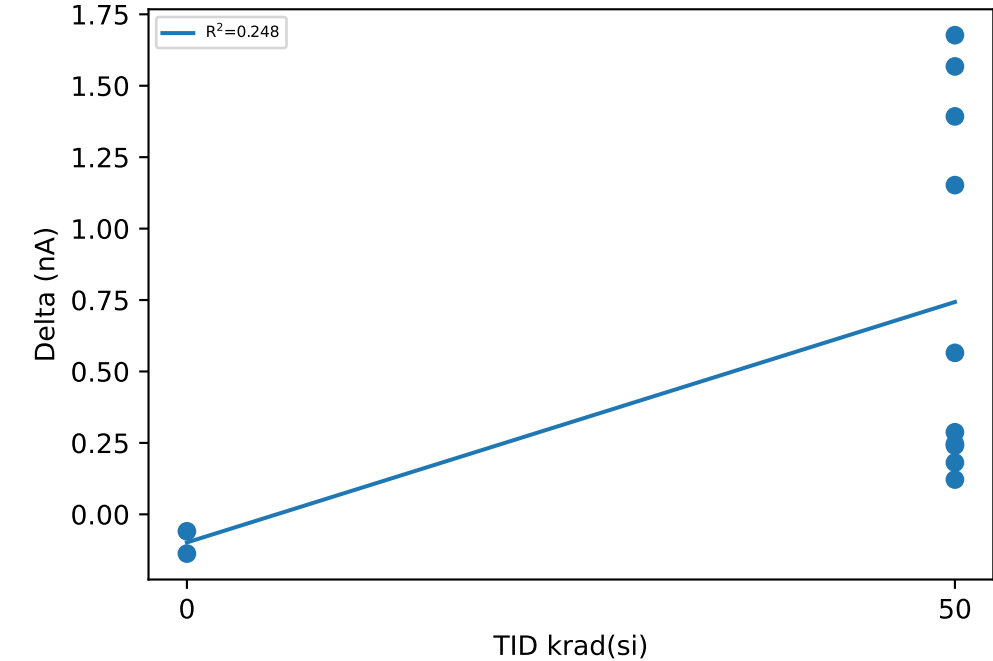
TID vs Result Stats



Test Results (Lower Limit = -35.0, Upper Limit = 250.0 (nA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5381	0.4007	-0.1374
2	0	Correlation	0.5256	0.4663	-0.0593
4	50	Bias	0.8066	2.3742	1.5676
6	50	Bias	0.4319	0.6724	0.2405
7	50	Bias	0.4819	0.7692	0.2873
8	50	Bias	1.7903	2.9425	1.1522
9	50	Bias	0.7879	2.1806	1.3927
11	50	Unbias	0.3695	0.6161	0.2466
12	50	Unbias	0.535	1.1002	0.5652
13	50	Unbias	0.4475	0.6286	0.1811
14	50	Unbias	0.4663	0.588	0.1217
15	50	Unbias	0.8097	2.4866	1.6769

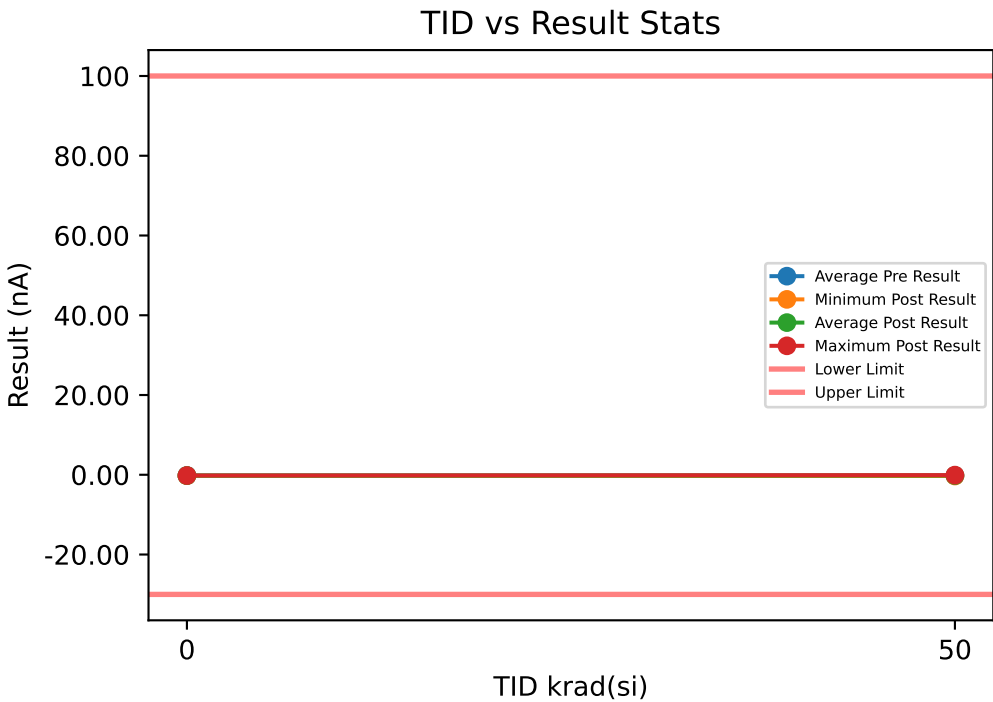
TID vs Post - Pre Exposure Delta



Test Statistics (nA)

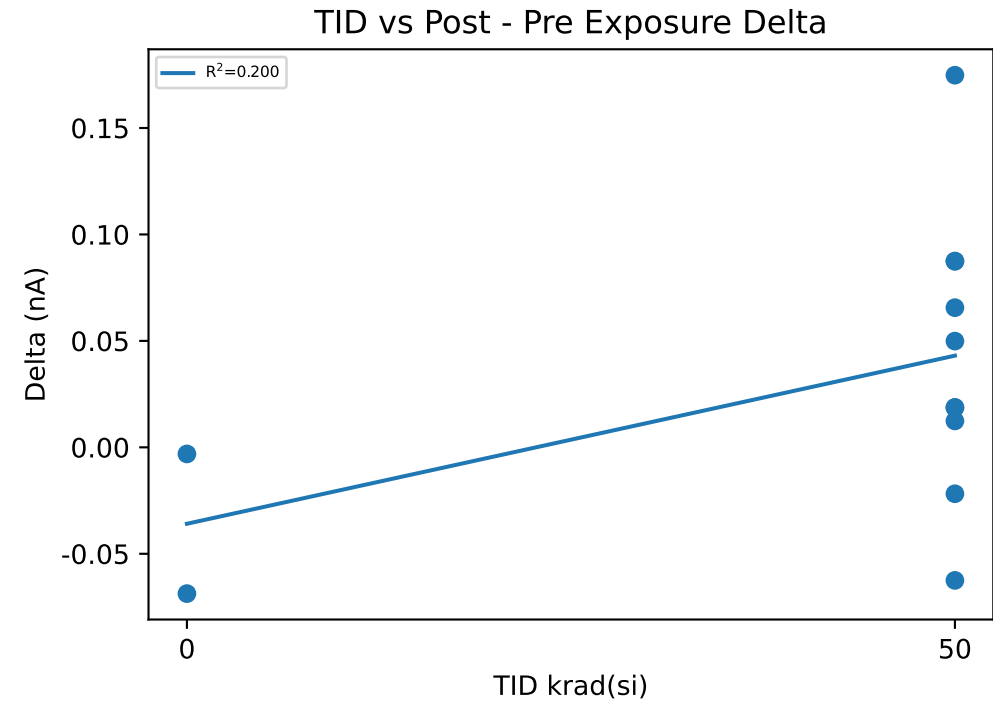
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5256	0.53185	0.5381	0.0088388	0.4007	0.4335	0.4663	0.046386	-0.1374	-0.09835	-0.0593	0.055225
50	0.3695	0.69266	1.7903	0.42079	0.588	1.4358	2.9425	0.94232	0.1217	0.74318	1.6769	0.63084

Device Test: 16.17 I_EN_LEAK_1V(LEAK|EN_LEAK/EN/14/14/0/1000/5/500kHz//@I_EN_LEAK_1V)



Test Results (Lower Limit = -30.0, Upper Limit = 100.0 (nA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	-0.227	-0.2301	-0.0031
2	0	Correlation	-0.1239	-0.1926	-0.0687
4	50	Bias	-0.2801	-0.1926	0.0875
6	50	Bias	-0.2582	-0.1926	0.0656
7	50	Bias	-0.2145	-0.2363	-0.0218
8	50	Bias	-0.1645	-0.1146	0.0499
9	50	Bias	-0.1957	-0.177	0.0187
11	50	Unbias	-0.2488	-0.1614	0.0874
12	50	Unbias	-0.1926	-0.1739	0.0187
13	50	Unbias	-0.2488	-0.3113	-0.0625
14	50	Unbias	-0.2363	-0.2239	0.0124
15	50	Unbias	-0.2613	-0.0865	0.1748

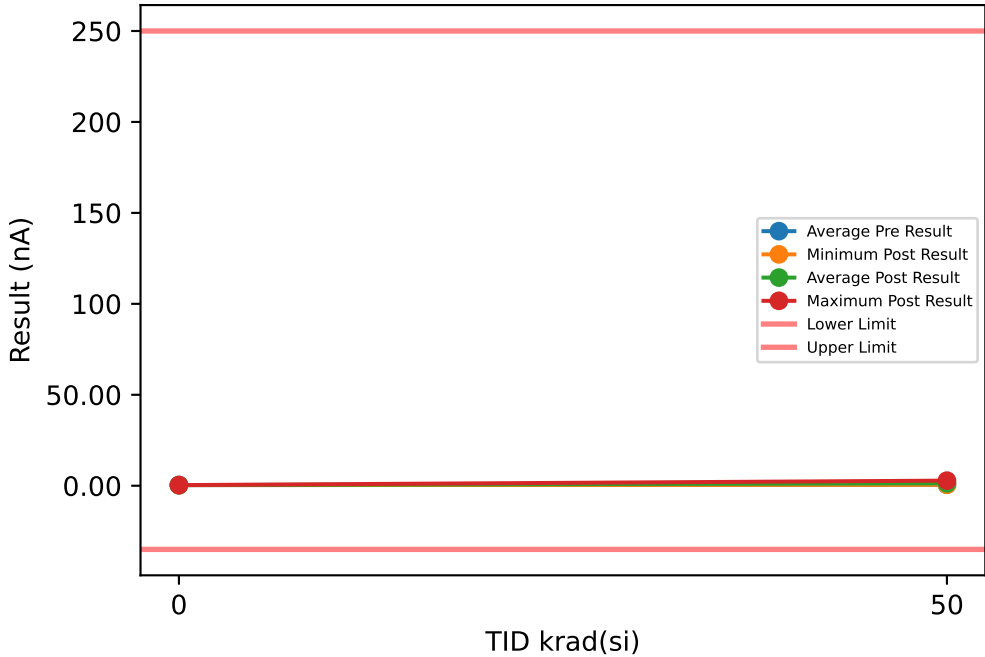


Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.227	-0.17545	-0.1239	0.072903	-0.2301	-0.21135	-0.1926	0.026517	-0.0687	-0.0359	-0.0031	0.046386
50	-0.2801	-0.23008	-0.1645	0.036723	-0.3113	-0.18701	-0.0865	0.06287	-0.0625	0.04307	0.1748	0.066104

Device Test: 16.18 I_EN_LEAK(LEAK|EN_LEAK/EN/14/14/0/1000/5/500kHz//@I_EN_LEAK)

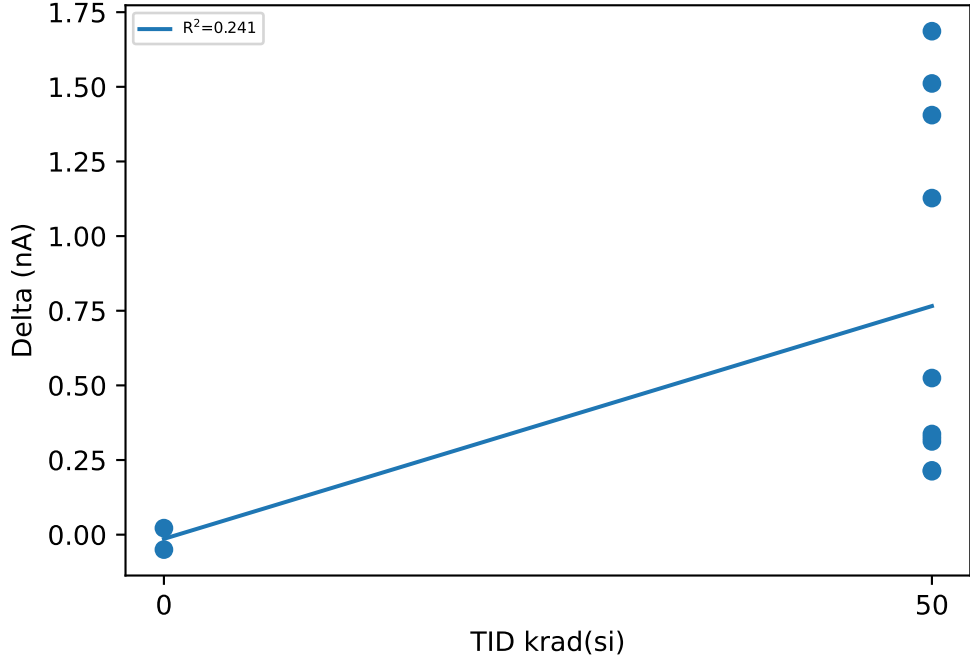
TID vs Result Stats



Test Results (Lower Limit = -35.0, Upper Limit = 250.0 (nA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.3257	0.3476	0.0219
2	0	Correlation	0.3851	0.3351	-0.05
4	50	Bias	0.5755	2.2618	1.6863
6	50	Bias	0.3382	0.663	0.3248
7	50	Bias	0.3476	0.6848	0.3372
8	50	Bias	1.6778	2.8051	1.1273
9	50	Bias	0.613	2.0182	1.4052
11	50	Unbias	0.3101	0.5225	0.2124
12	50	Unbias	0.4694	0.994	0.5246
13	50	Unbias	0.3164	0.5318	0.2154
14	50	Unbias	0.257	0.5693	0.3123
15	50	Unbias	0.7161	2.2274	1.5113

TID vs Post - Pre Exposure Delta

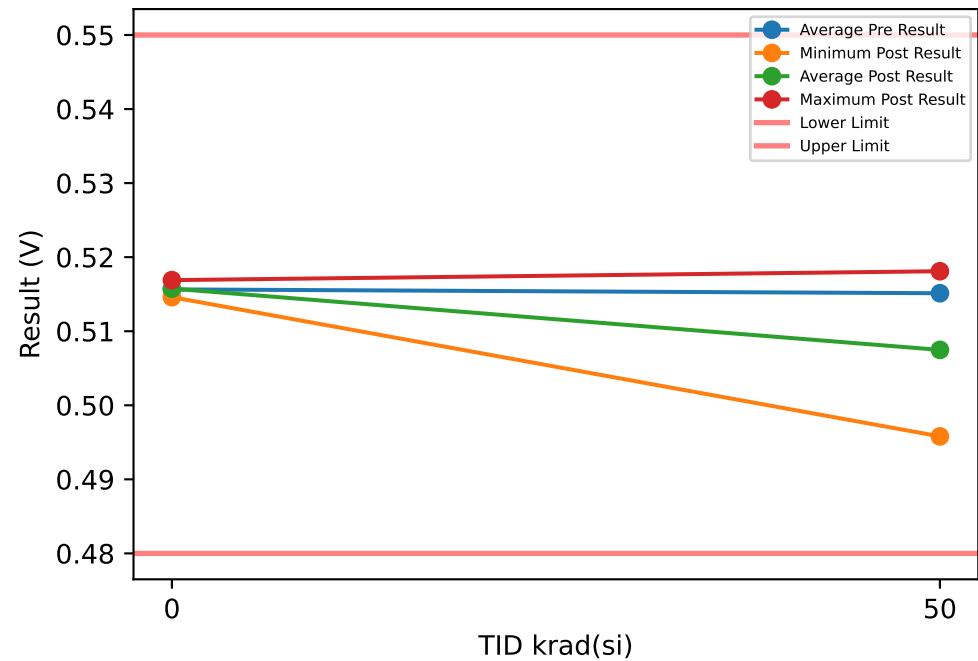


Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.3257	0.3554	0.3851	0.042002	0.3351	0.34135	0.3476	0.0088388	-0.05	-0.01405	0.0219	0.050841
50	0.257	0.56211	1.6778	0.42071	0.5225	1.3278	2.8051	0.89225	0.2124	0.76568	1.6863	0.59571

Device Test: 16.2 V_EN_FALL(LEVEL|EN_FALL/EN/4.5/4.5/0/0/4.5/500kHz//@V_EN_FALL)

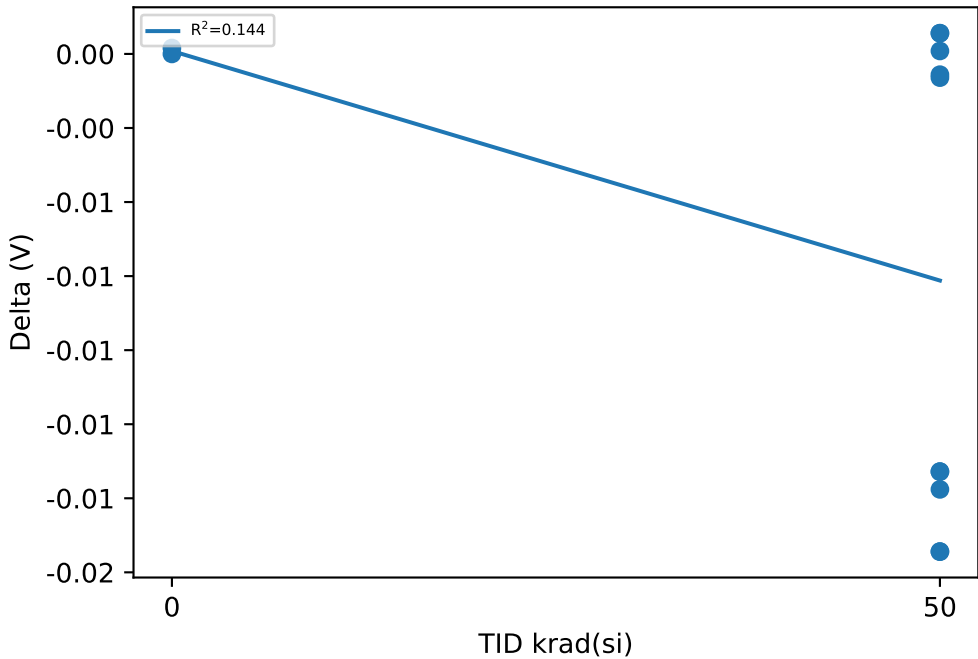
TID vs Result Stats



Test Results (Lower Limit = 0.48, Upper Limit = 0.55 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5167	0.5169	0.0002
2	0	Correlation	0.5146	0.5146	0
4	50	Bias	0.5105	0.4958	-0.0147
6	50	Bias	0.5146	0.4978	-0.0168
7	50	Bias	0.5154	0.5013	-0.0141
8	50	Bias	0.5146	0.5005	-0.0141
9	50	Bias	0.5154	0.4986	-0.0168
11	50	Unbias	0.514	0.5132	-0.0008
12	50	Unbias	0.5166	0.5167	0.0001
13	50	Unbias	0.5167	0.5174	0.0007
14	50	Unbias	0.5161	0.5154	-0.0007
15	50	Unbias	0.5174	0.5181	0.0007

TID vs Post - Pre Exposure Delta

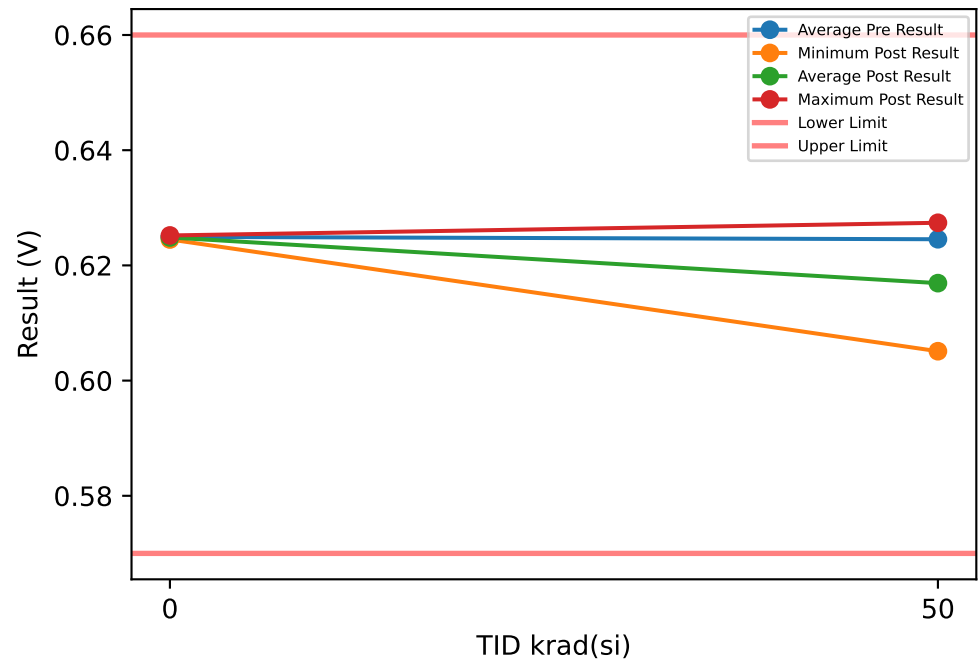


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5146	0.51565	0.5167	0.0014849	0.5146	0.51575	0.5169	0.0016263	0	0.0001	0.0002	0.00014142
50	0.5105	0.51513	0.5174	0.0019477	0.4958	0.50748	0.5181	0.0093544	-0.0168	-0.00765	0.0007	0.0081315

Device Test: 16.4 V_EN_RISE(LEVEL|EN_RISE/EN/5/5/0/0/5/500kHz//@V_EN_RISE)

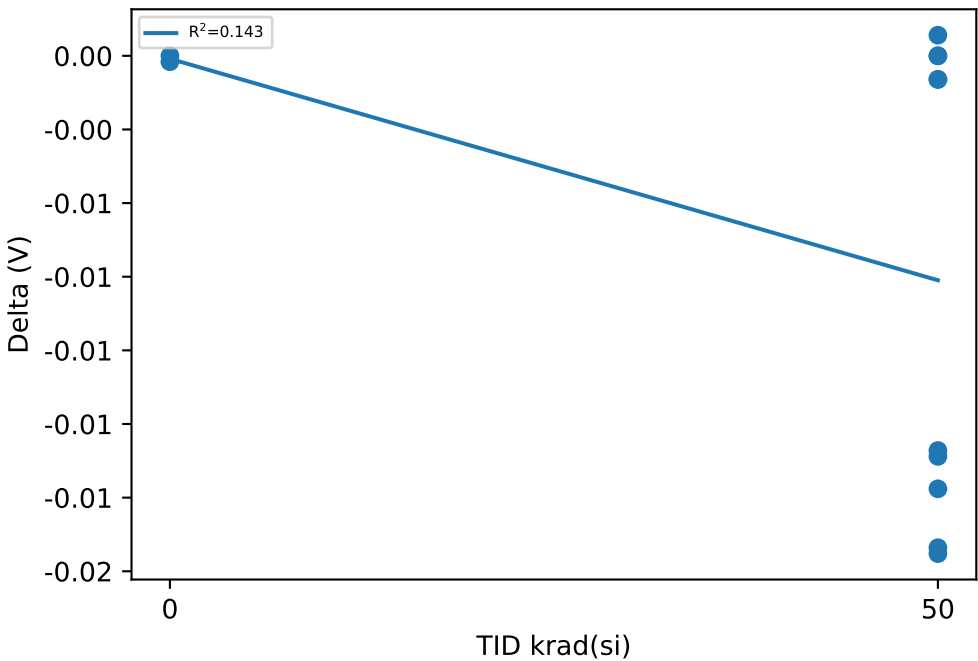
TID vs Result Stats



Test Results (Lower Limit = 0.57, Upper Limit = 0.66 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.6252	0.6252	0
2	0	Correlation	0.6247	0.6245	-0.0002
4	50	Bias	0.6198	0.6051	-0.0147
6	50	Bias	0.6247	0.6078	-0.0169
7	50	Bias	0.6247	0.6111	-0.0136
8	50	Bias	0.6232	0.6098	-0.0134
9	50	Bias	0.6245	0.6078	-0.0167
11	50	Unbias	0.6233	0.6225	-0.0008
12	50	Unbias	0.6265	0.6265	0
13	50	Unbias	0.6267	0.6267	0
14	50	Unbias	0.6253	0.6245	-0.0008
15	50	Unbias	0.6267	0.6274	0.0007

TID vs Post - Pre Exposure Delta

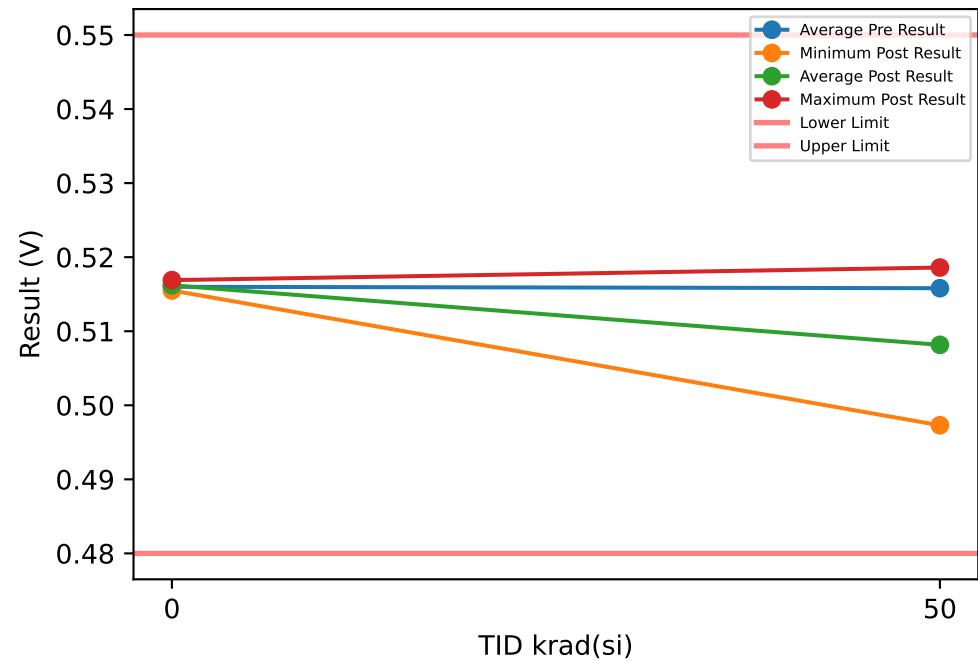


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6247	0.62495	0.6252	0.00035355	0.6245	0.62485	0.6252	0.00049497	-0.0002	-0.0001	0	0.00014142
50	0.6198	0.62454	0.6267	0.0020977	0.6051	0.61692	0.6274	0.0092884	-0.0169	-0.00762	0.0007	0.0079319

Device Test: 16.5 V_EN_FALL(LEVEL|EN_FALL/EN/5/5/0/0/5/500kHz//@V_EN_FALL)

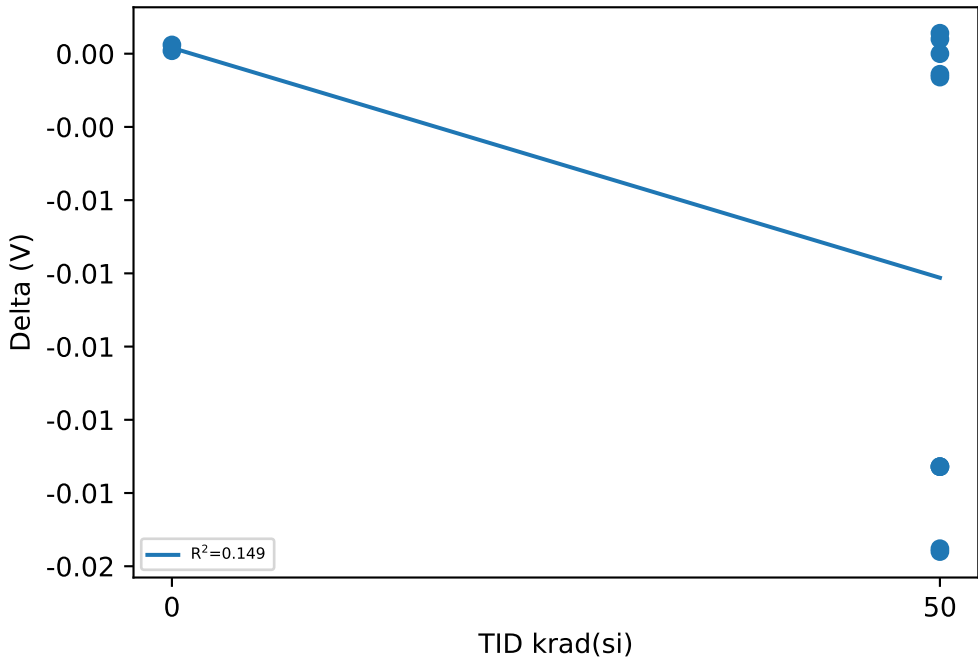
TID vs Result Stats



Test Results (Lower Limit = 0.48, Upper Limit = 0.55 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5166	0.5169	0.0003
2	0	Correlation	0.5154	0.5155	0.0001
4	50	Bias	0.5114	0.4973	-0.0141
6	50	Bias	0.5154	0.4984	-0.017
7	50	Bias	0.516	0.5019	-0.0141
8	50	Bias	0.5154	0.5013	-0.0141
9	50	Bias	0.5154	0.4985	-0.0169
11	50	Unbias	0.5147	0.514	-0.0007
12	50	Unbias	0.5174	0.5174	0
13	50	Unbias	0.5174	0.5181	0.0007
14	50	Unbias	0.5169	0.5161	-0.0008
15	50	Unbias	0.5181	0.5186	0.0005

TID vs Post - Pre Exposure Delta

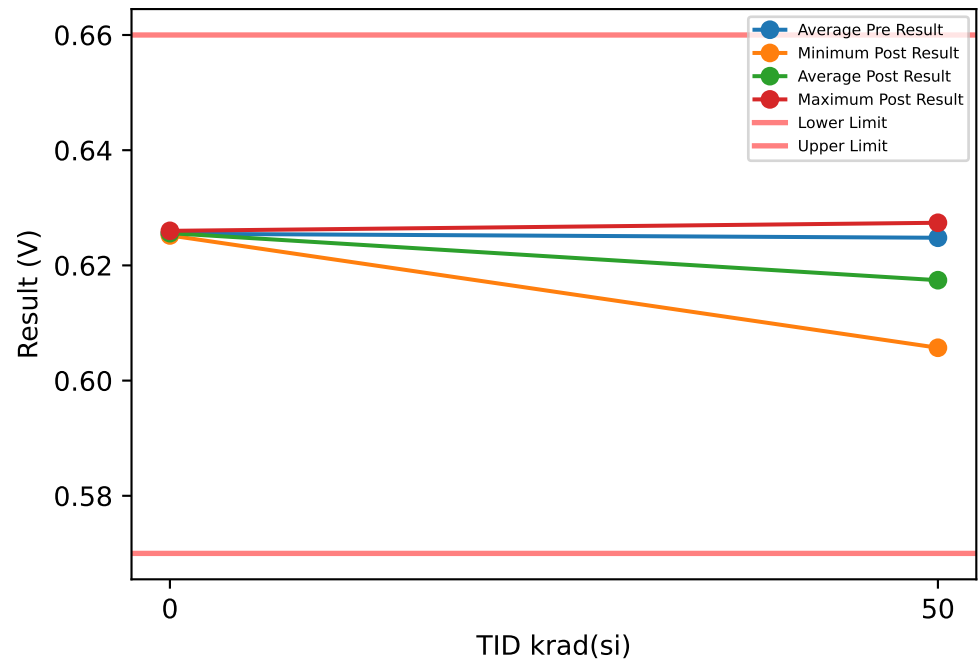


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5154	0.516	0.5166	0.00084853	0.5155	0.5162	0.5169	0.00098995	0.0001	0.0002	0.0003	0.00014142
50	0.5114	0.51581	0.5181	0.0019064	0.4973	0.50816	0.5186	0.0093279	-0.017	-0.00765	0.0007	0.0080807

Device Test: 16.7 V_EN_RISE(LEVEL|EN_RISE/EN/12/12/0/0/5/500kHz//@V_EN_RISE)

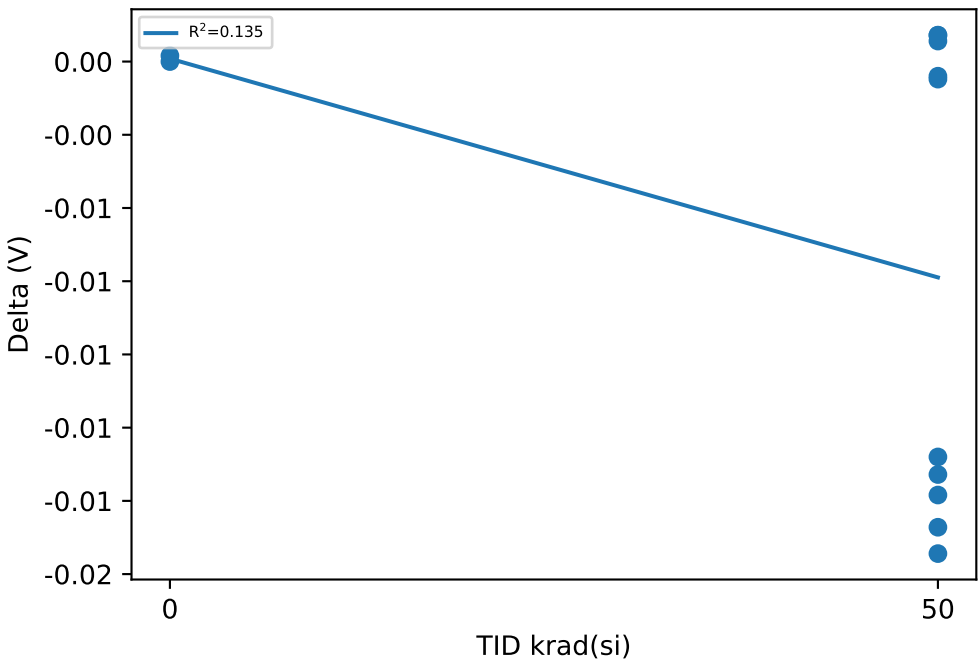
TID vs Result Stats



Test Results (Lower Limit = 0.57, Upper Limit = 0.66 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.6258	0.626	0.0002
2	0	Correlation	0.6252	0.6252	0
4	50	Bias	0.6205	0.6057	-0.0148
6	50	Bias	0.6245	0.6077	-0.0168
7	50	Bias	0.6252	0.6111	-0.0141
8	50	Bias	0.6239	0.6104	-0.0135
9	50	Bias	0.6245	0.6086	-0.0159
11	50	Unbias	0.6238	0.6233	-0.0005
12	50	Unbias	0.6267	0.6274	0.0007
13	50	Unbias	0.6265	0.6274	0.0009
14	50	Unbias	0.6259	0.6253	-0.0006
15	50	Unbias	0.6265	0.6274	0.0009

TID vs Post - Pre Exposure Delta

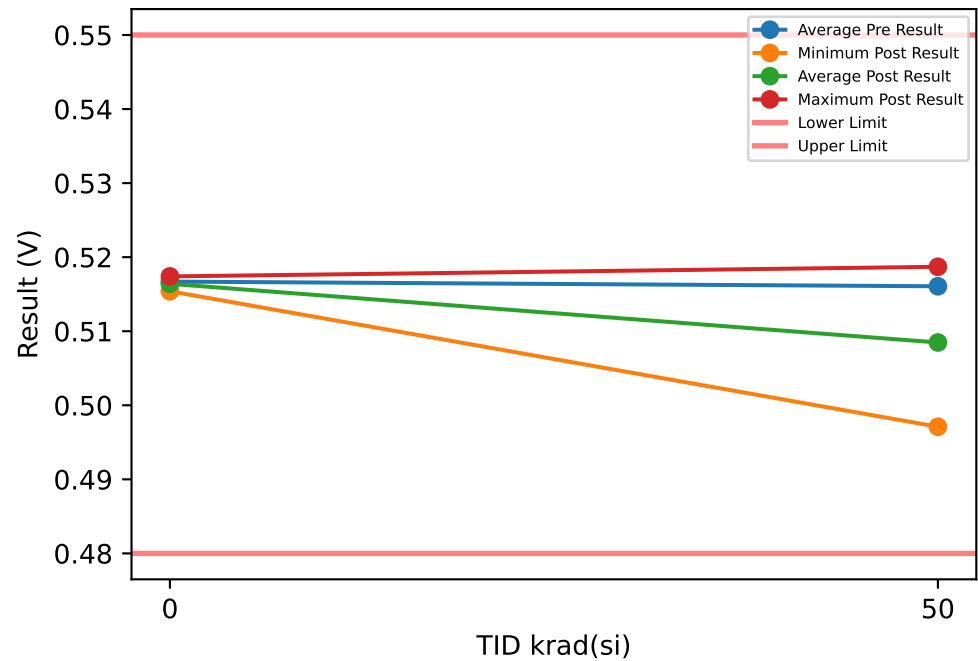


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6252	0.6255	0.6258	0.00042426	0.6252	0.6256	0.626	0.00056569	0	0.0001	0.0002	0.00014142
50	0.6205	0.6248	0.6267	0.0018631	0.6057	0.61743	0.6274	0.0093946	-0.0168	-0.00737	0.0009	0.0081288

Device Test: 16.8 V_EN_FALL(LEVEL|EN_FALL/EN/12/12/0/0/5/500kHz//@V_EN_FALL)

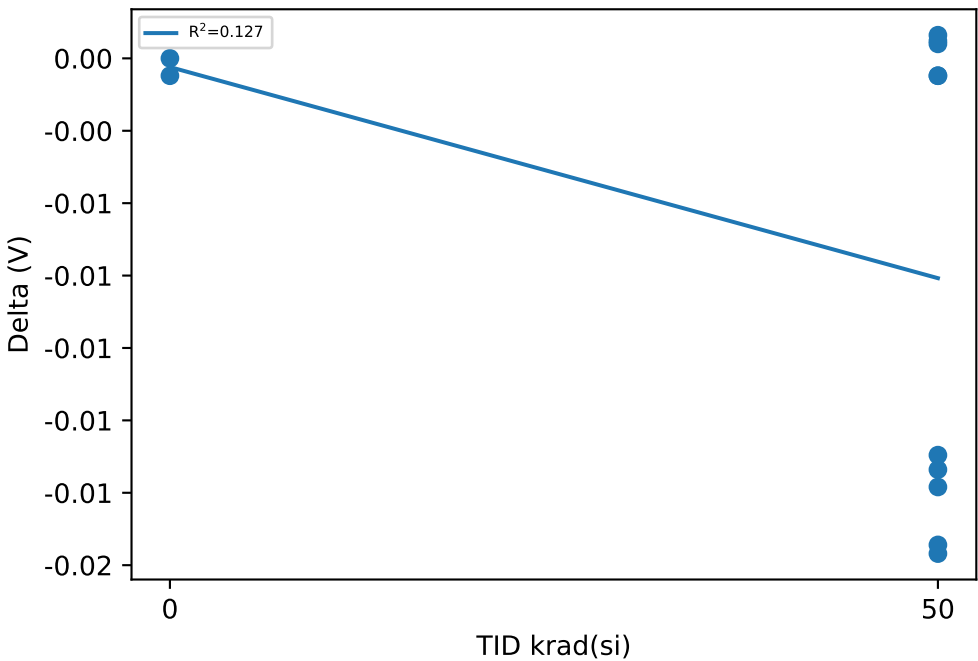
TID vs Result Stats



Test Results (Lower Limit = 0.48, Upper Limit = 0.55 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5174	0.5174	0
2	0	Correlation	0.516	0.5154	-0.0006
4	50	Bias	0.5119	0.4971	-0.0148
6	50	Bias	0.5161	0.499	-0.0171
7	50	Bias	0.5167	0.5025	-0.0142
8	50	Bias	0.5155	0.5018	-0.0137
9	50	Bias	0.5161	0.4993	-0.0168
11	50	Unbias	0.5146	0.514	-0.0006
12	50	Unbias	0.5174	0.5182	0.0008
13	50	Unbias	0.5176	0.5181	0.0005
14	50	Unbias	0.5167	0.5161	-0.0006
15	50	Unbias	0.5181	0.5187	0.0006

TID vs Post - Pre Exposure Delta

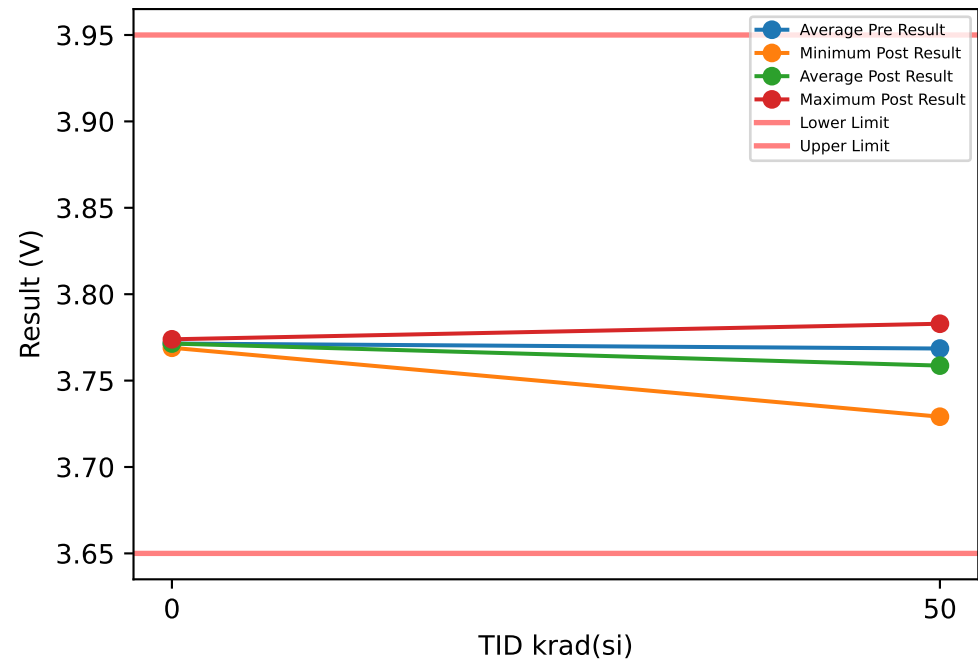


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.516	0.5167	0.5174	0.00098995	0.5154	0.5164	0.5174	0.0014142	-0.0006	-0.0003	0	0.00042426
50	0.5119	0.51607	0.5181	0.001792	0.4971	0.50848	0.5187	0.0092137	-0.0171	-0.00759	0.0008	0.0082254

Device Test: 17.1 PVIN_UVLO_RISE(UVLO|PVIN_RISE/PVIN/4.5/4.5/0/1000/4.5/100kHz//@PVIN_UVLO_RISE)

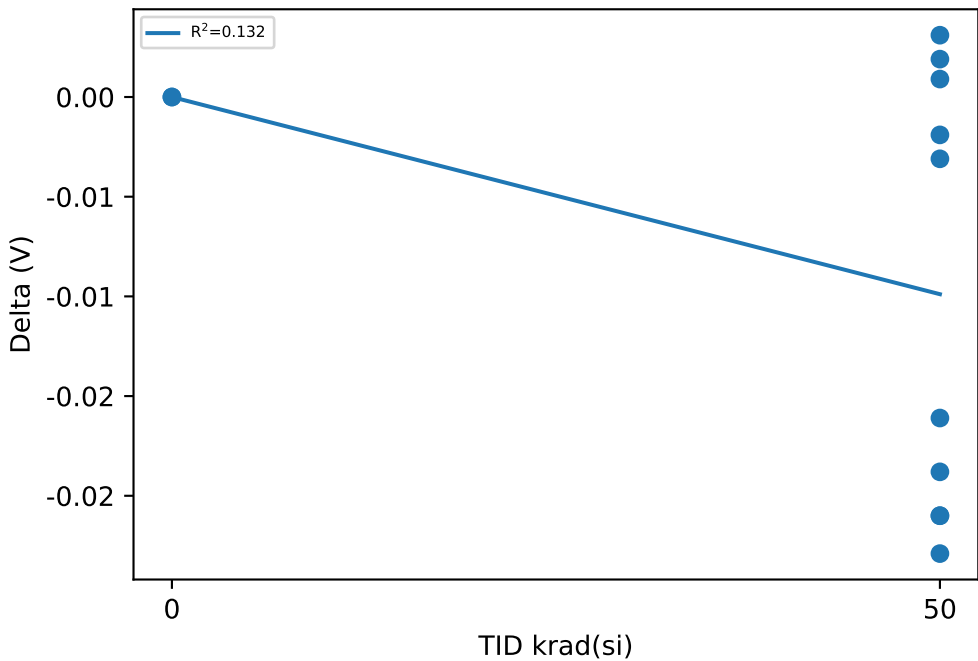
TID vs Result Stats



Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.7739	3.7739	0
2	0	Correlation	3.769	3.769	0
4	50	Bias	3.752	3.7291	-0.0229
6	50	Bias	3.7578	3.739	-0.0188
7	50	Bias	3.7739	3.7578	-0.0161
8	50	Bias	3.768	3.747	-0.021
9	50	Bias	3.7779	3.7569	-0.021
11	50	Unbias	3.7761	3.773	-0.0031
12	50	Unbias	3.782	3.7801	-0.0019
13	50	Unbias	3.7569	3.76	0.0031
14	50	Unbias	3.76	3.7609	0.0009
15	50	Unbias	3.781	3.7829	0.0019

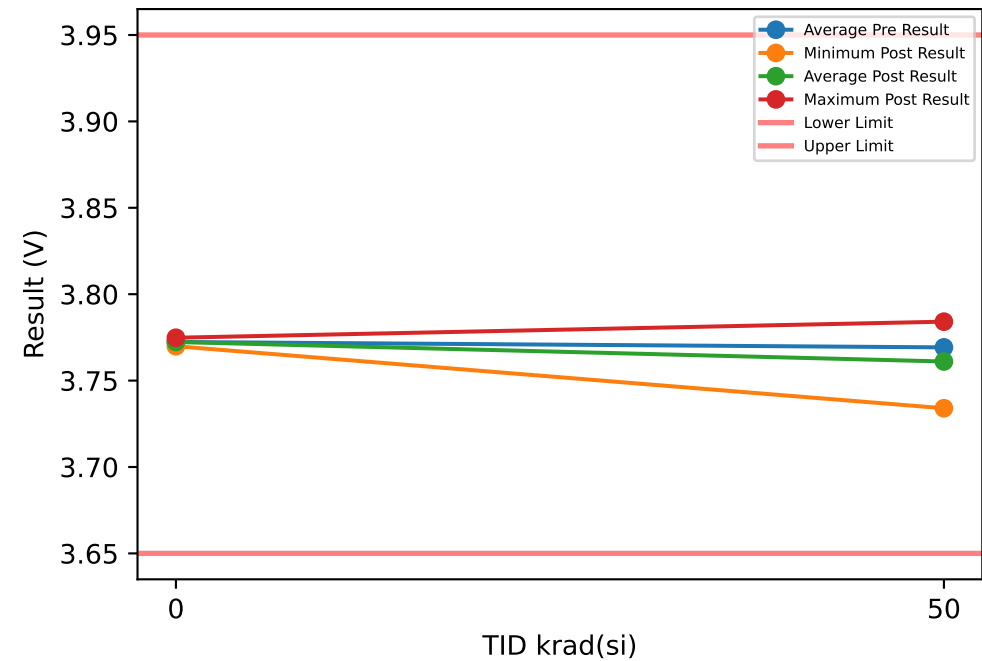
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.769	3.7714	3.7739	0.0034648	3.769	3.7714	3.7739	0.0034648	0	0	0	0
50	3.752	3.7686	3.782	0.011093	3.7291	3.7587	3.7829	0.017191	-0.0229	-0.00989	0.0031	0.010894

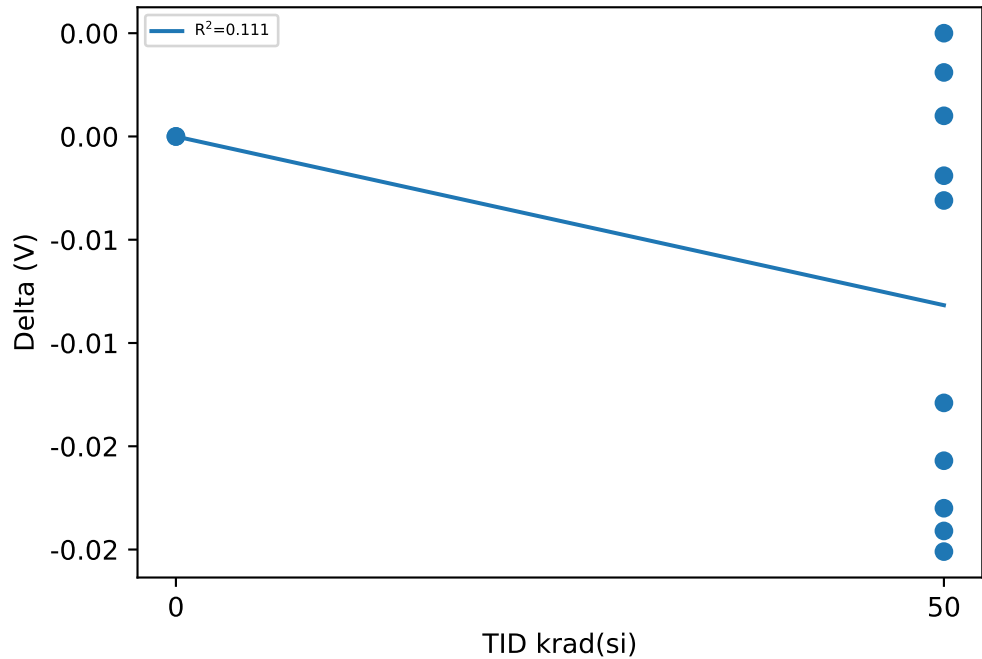
TID vs Result Stats



Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.7748	3.7748	0
2	0	Correlation	3.7699	3.7699	0
4	50	Bias	3.752	3.734	-0.018
6	50	Bias	3.7578	3.7449	-0.0129
7	50	Bias	3.7748	3.7591	-0.0157
8	50	Bias	3.768	3.7489	-0.0191
9	50	Bias	3.7779	3.7578	-0.0201
11	50	Unbias	3.777	3.7739	-0.0031
12	50	Unbias	3.7829	3.781	-0.0019
13	50	Unbias	3.76	3.765	0.005
14	50	Unbias	3.7609	3.7619	0.001
15	50	Unbias	3.781	3.7841	0.0031

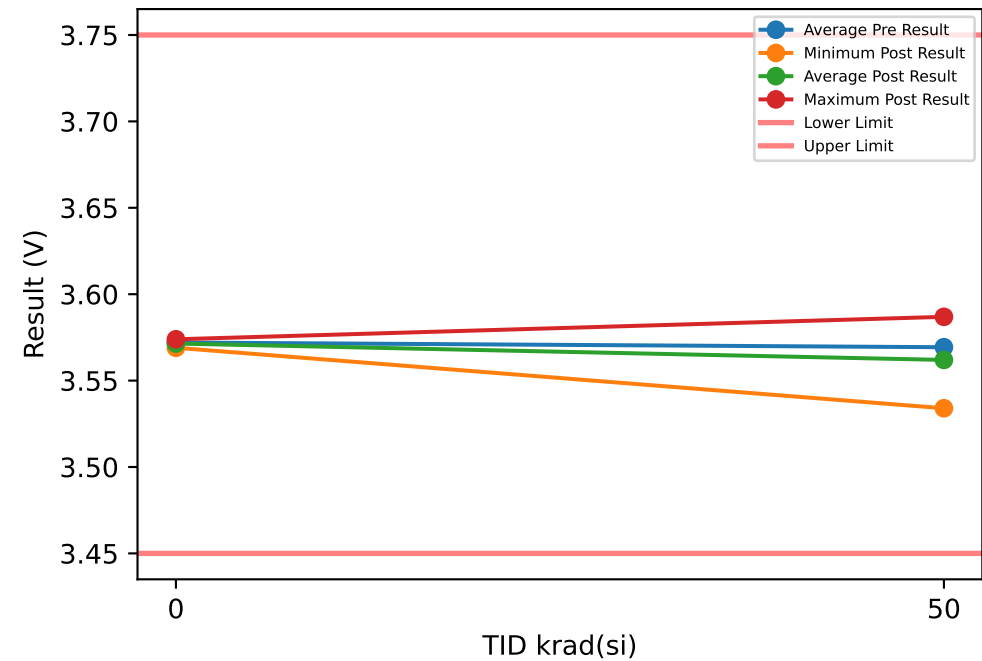
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7699	3.7723	3.7748	0.0034648	3.7699	3.7723	3.7748	0.0034648	0	0	0	0
50	3.752	3.7692	3.7829	0.010932	3.734	3.7611	3.7841	0.015865	-0.0201	-0.00817	0.005	0.0099279

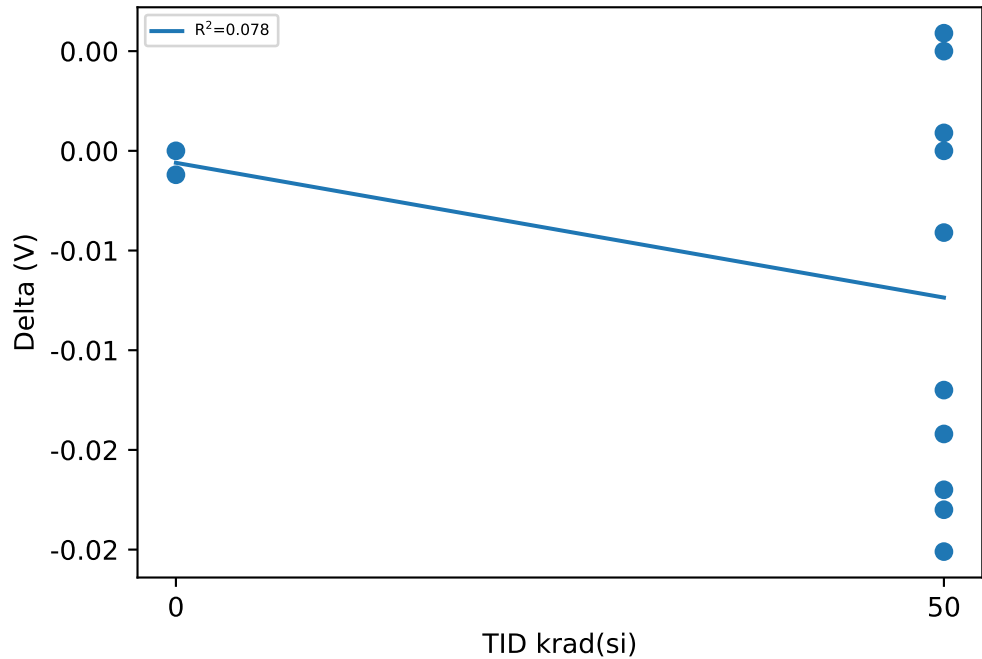
TID vs Result Stats



Test Results (Lower Limit = 3.45, Upper Limit = 3.75 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.5751	3.5739	-0.0012
2	0	Correlation	3.569	3.569	0
4	50	Bias	3.5541	3.534	-0.0201
6	50	Bias	3.5581	3.5461	-0.012
7	50	Bias	3.5751	3.5609	-0.0142
8	50	Bias	3.569	3.551	-0.018
9	50	Bias	3.577	3.56	-0.017
11	50	Unbias	3.5761	3.572	-0.0041
12	50	Unbias	3.581	3.581	0
13	50	Unbias	3.56	3.5659	0.0059
14	50	Unbias	3.5609	3.5618	0.0009
15	50	Unbias	3.5819	3.5869	0.005

TID vs Post - Pre Exposure Delta

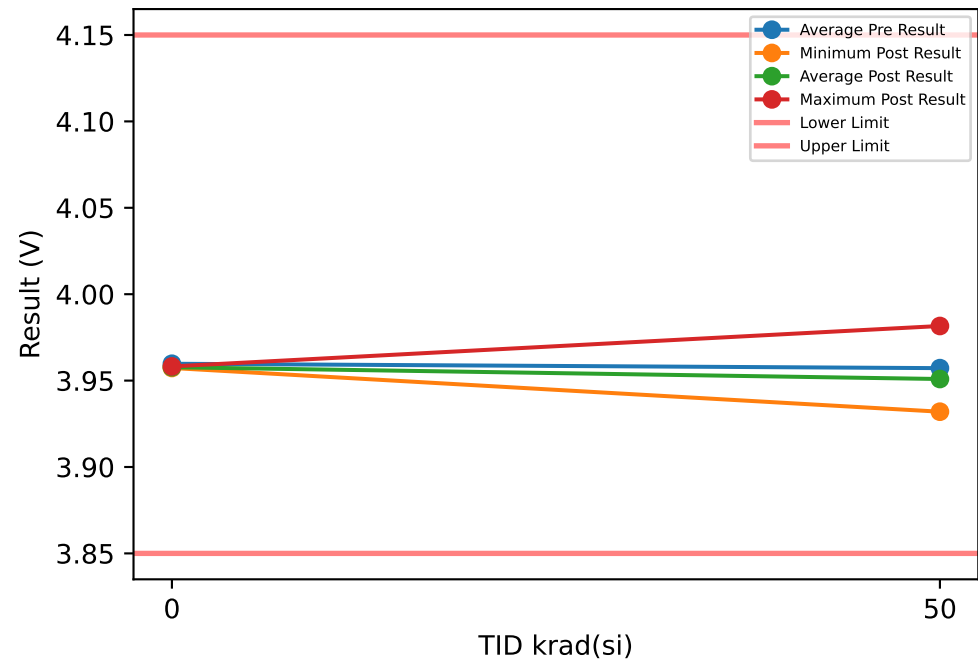


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.569	3.572	3.5751	0.0043134	3.569	3.5715	3.5739	0.0034648	-0.0012	-0.0006	0	0.00084853
50	3.5541	3.5693	3.5819	0.010266	3.534	3.562	3.5869	0.015844	-0.0201	-0.00736	0.0059	0.009991

Device Test: 17.13 VIN_UVLO_RISE(UVLO|VIN_RISE/VIN/4.5/4.5/0/1000/4.5/500kHz//@VIN_UVLO_RISE)

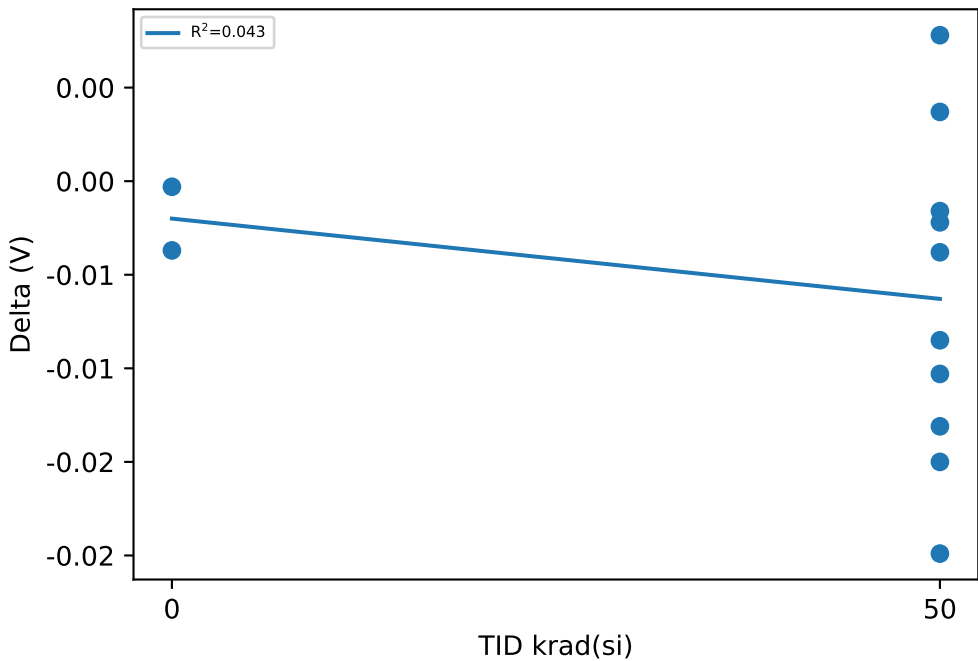
TID vs Result Stats



Test Results (Lower Limit = 3.85, Upper Limit = 4.15 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.9585	3.9582	-0.0003
2	0	Correlation	3.961	3.9573	-0.0037
4	50	Bias	3.9519	3.932	-0.0199
6	50	Bias	3.9476	3.9391	-0.0085
7	50	Bias	3.9504	3.9354	-0.015
8	50	Bias	3.9526	3.9423	-0.0103
9	50	Bias	3.9607	3.9476	-0.0131
11	50	Unbias	3.9738	3.9816	0.0078
12	50	Unbias	3.9573	3.9557	-0.0016
13	50	Unbias	3.9548	3.9526	-0.0022
14	50	Unbias	3.9573	3.9535	-0.0038
15	50	Unbias	3.9657	3.9694	0.0037

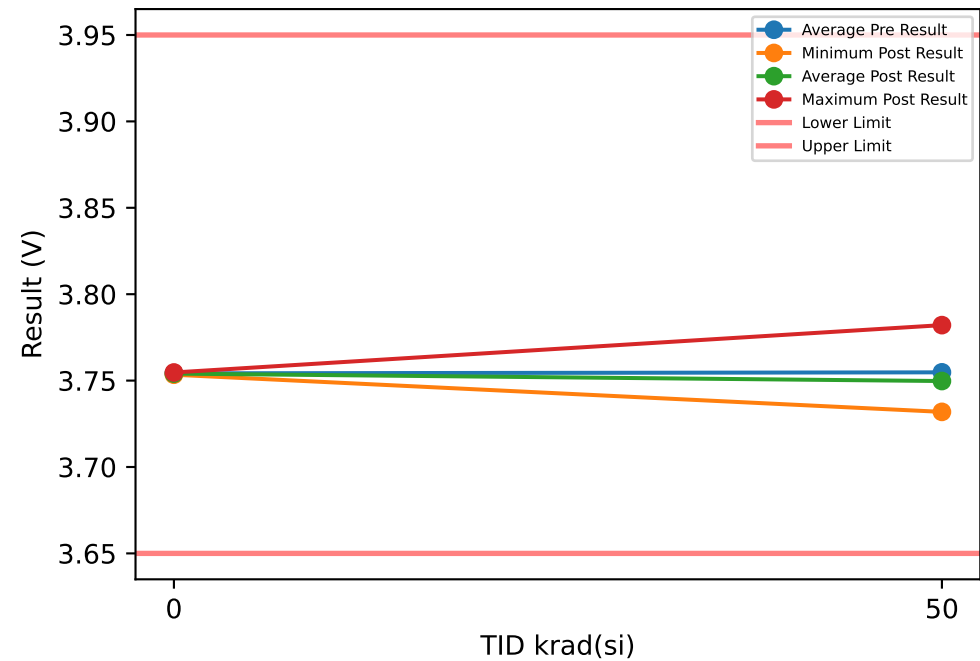
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.9585	3.9597	3.961	0.0017678	3.9573	3.9577	3.9582	0.0006364	-0.0037	-0.002	-0.0003	0.0024042
50	3.9476	3.9572	3.9738	0.0078421	3.932	3.9509	3.9816	0.015416	-0.0199	-0.00629	0.0078	0.008639

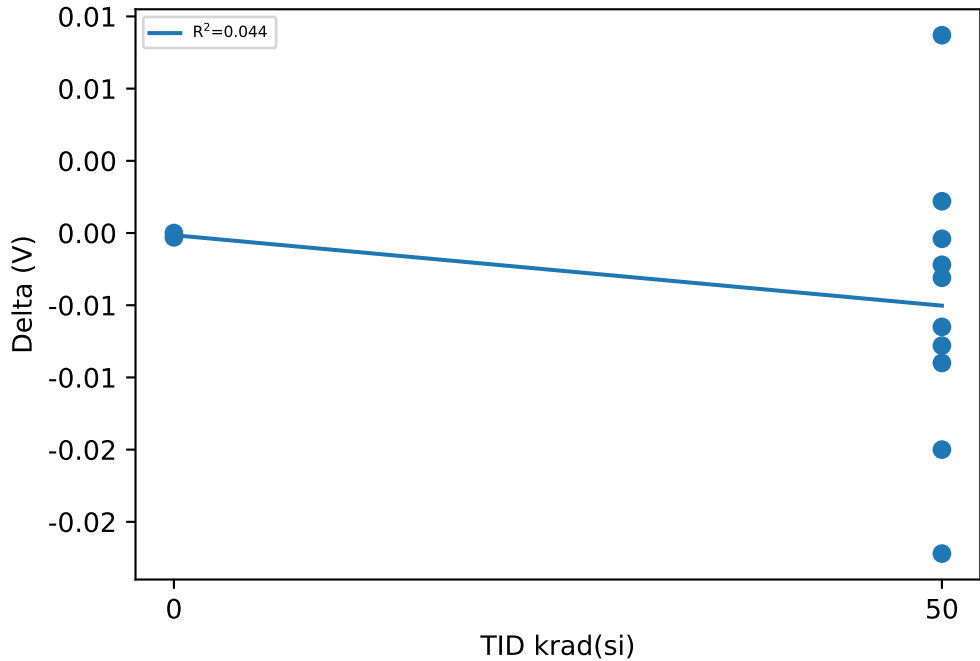
TID vs Result Stats



Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.7547	3.7547	0
2	0	Correlation	3.7537	3.7534	-0.0003
4	50	Bias	3.7541	3.7319	-0.0222
6	50	Bias	3.7478	3.7388	-0.009
7	50	Bias	3.7497	3.7347	-0.015
8	50	Bias	3.7506	3.7428	-0.0078
9	50	Bias	3.7537	3.7472	-0.0065
11	50	Unbias	3.7684	3.7821	0.0137
12	50	Unbias	3.7541	3.7537	-0.0004
13	50	Unbias	3.7519	3.7497	-0.0022
14	50	Unbias	3.7578	3.7547	-0.0031
15	50	Unbias	3.7597	3.7619	0.0022

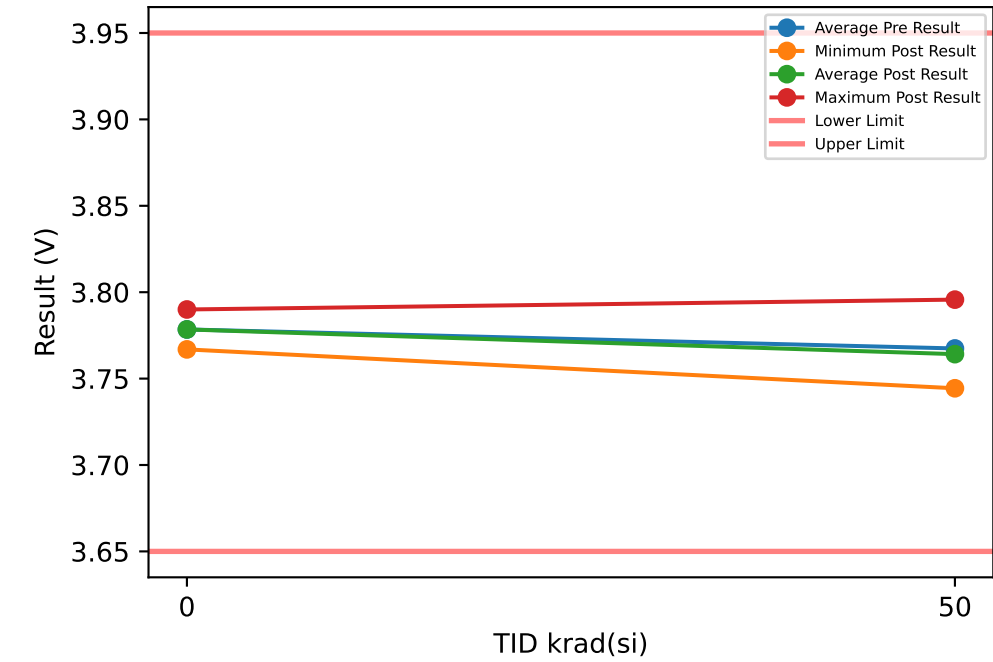
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7537	3.7542	3.7547	0.00070711	3.7534	3.7541	3.7547	0.00091924	-0.0003	-0.00015	0	0.00021213
50	3.7478	3.7548	3.7684	0.0059742	3.7319	3.7498	3.7821	0.014735	-0.0222	-0.00503	0.0137	0.0097528

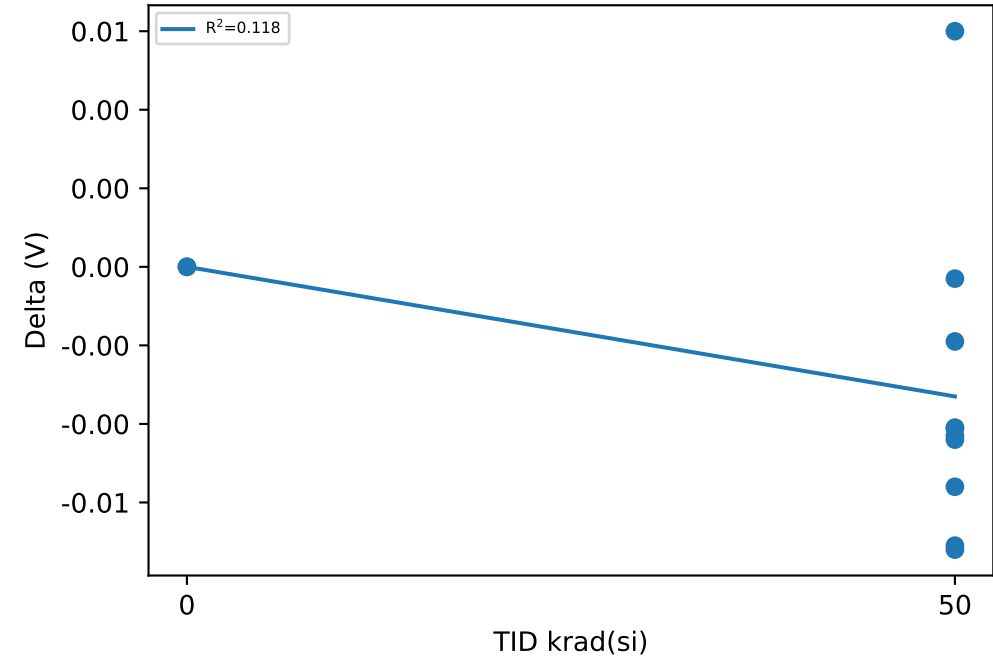
TID vs Result Stats



Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.7669	3.7669	0
2	0	Correlation	3.79	3.79	0
4	50	Bias	3.7588	3.7544	-0.0044
6	50	Bias	3.7707	3.7666	-0.0041
7	50	Bias	3.7669	3.7626	-0.0043
8	50	Bias	3.7485	3.7444	-0.0041
9	50	Bias	3.7566	3.751	-0.0056
11	50	Unbias	3.7897	3.7957	0.006
12	50	Unbias	3.7794	3.7775	-0.0019
13	50	Unbias	3.7704	3.7632	-0.0072
14	50	Unbias	3.7697	3.7626	-0.0071
15	50	Unbias	3.7638	3.7635	-0.0003

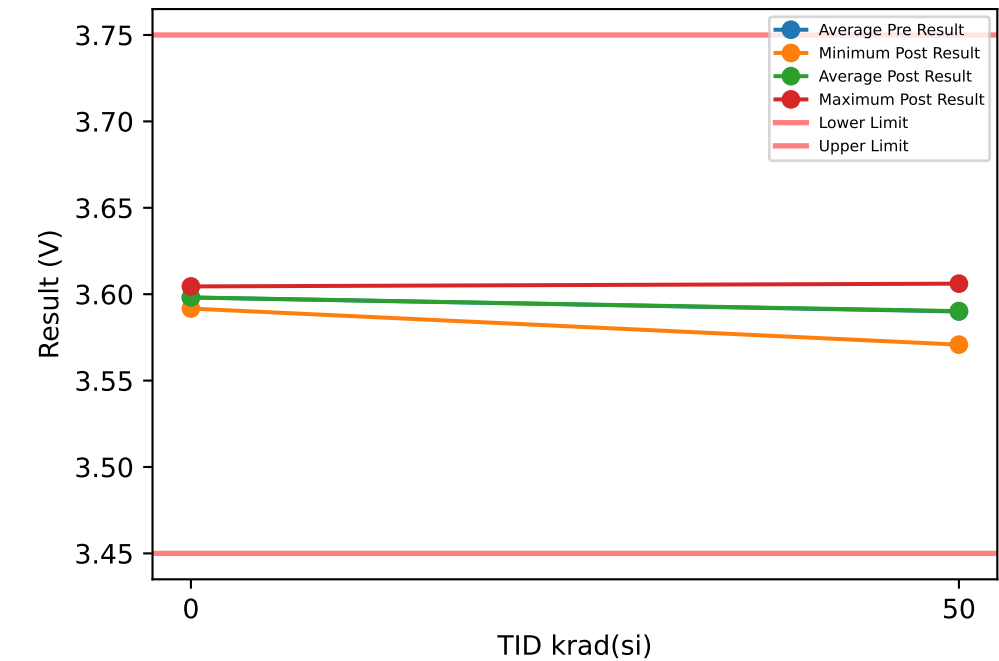
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7669	3.7785	3.79	0.016334	3.7669	3.7785	3.79	0.016334	0	0	0	0
50	3.7485	3.7675	3.7897	0.011678	3.7444	3.7641	3.7957	0.014313	-0.0072	-0.0033	0.006	0.0038856

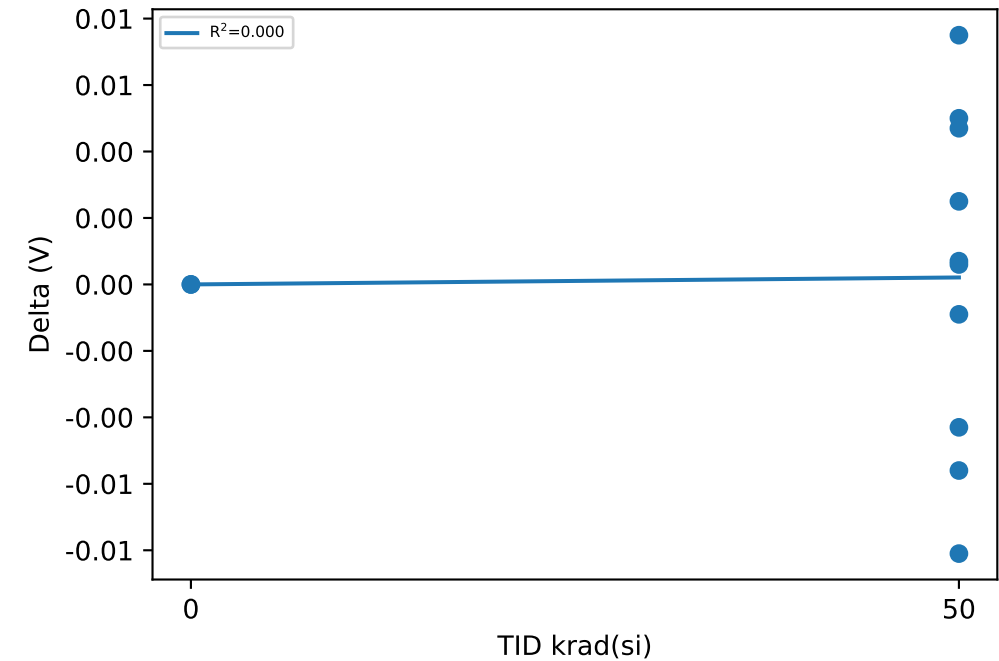
TID vs Result Stats



Test Results (Lower Limit = 3.45, Upper Limit = 3.75 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.5917	3.5917	0
2	0	Correlation	3.6045	3.6045	0
4	50	Bias	3.5936	3.5927	-0.0009
6	50	Bias	3.5799	3.5874	0.0075
7	50	Bias	3.5792	3.5799	0.0007
8	50	Bias	3.5789	3.5708	-0.0081
9	50	Bias	3.587	3.5827	-0.0043
11	50	Unbias	3.6117	3.6061	-0.0056
12	50	Unbias	3.5995	3.6045	0.005
13	50	Unbias	3.5974	3.598	0.0006
14	50	Unbias	3.587	3.5917	0.0047
15	50	Unbias	3.5858	3.5883	0.0025

TID vs Post - Pre Exposure Delta

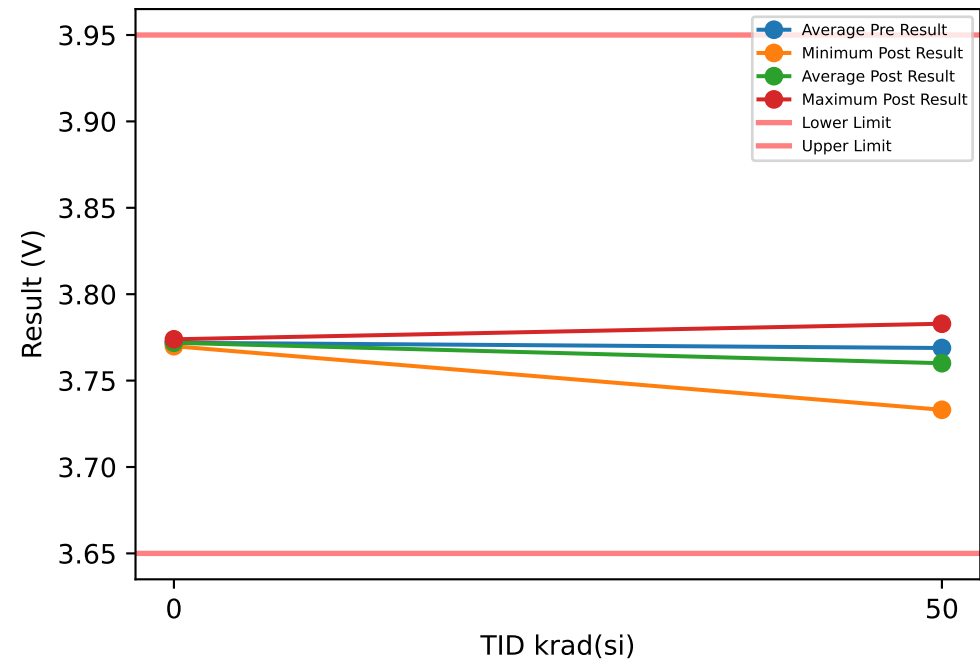


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5917	3.5981	3.6045	0.009051	3.5917	3.5981	3.6045	0.009051	0	0	0	0
50	3.5789	3.59	3.6117	0.010574	3.5708	3.5902	3.6061	0.010938	-0.0081	0.00021	0.0075	0.0050141

Device Test: 17.19 PVIN_UVLO_RISE(UVLO|PVIN_RISE/PVIN/4.5/4.5/0/1000/4.5/1MHz//@PVIN_UVLO_RISE)

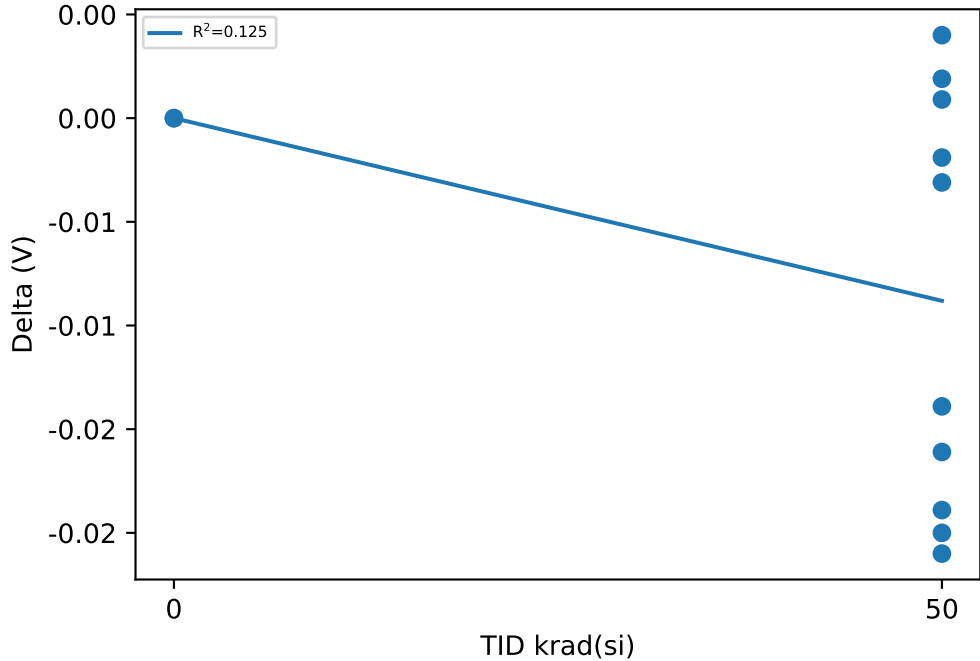
TID vs Result Stats



Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.7739	3.7739	0
2	0	Correlation	3.7699	3.7699	0
4	50	Bias	3.752	3.7331	-0.0189
6	50	Bias	3.7578	3.7439	-0.0139
7	50	Bias	3.7739	3.7578	-0.0161
8	50	Bias	3.768	3.748	-0.02
9	50	Bias	3.7779	3.7569	-0.021
11	50	Unbias	3.7761	3.773	-0.0031
12	50	Unbias	3.782	3.7801	-0.0019
13	50	Unbias	3.76	3.764	0.004
14	50	Unbias	3.76	3.7609	0.0009
15	50	Unbias	3.781	3.7829	0.0019

TID vs Post - Pre Exposure Delta

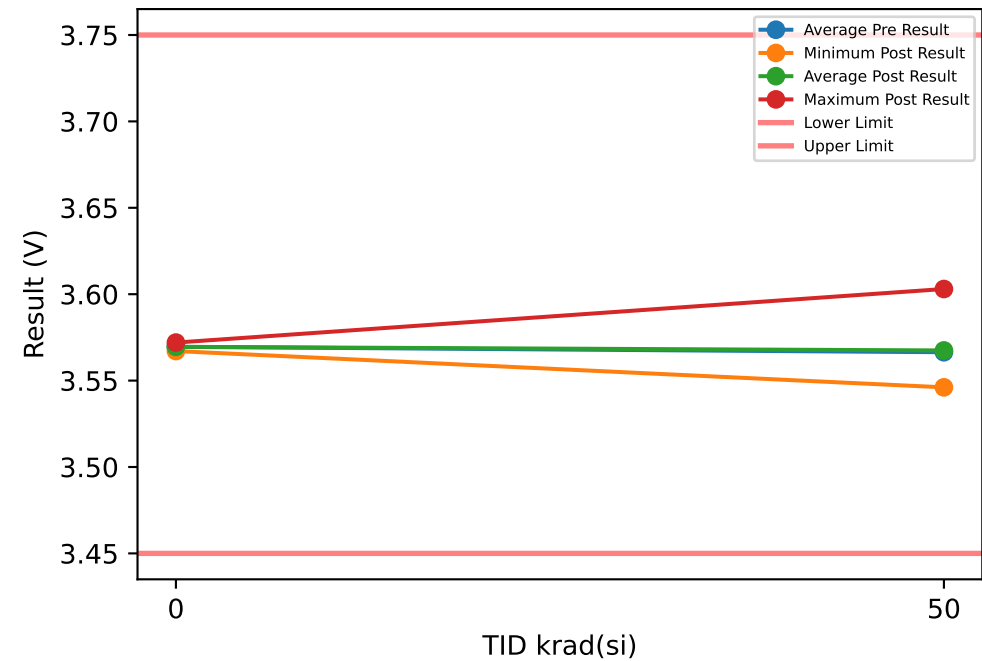


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7699	3.7719	3.7739	0.0028284	3.7699	3.7719	3.7739	0.0028284	0	0	0	0
50	3.752	3.7689	3.782	0.01077	3.7331	3.7601	3.7829	0.015831	-0.021	-0.00881	0.004	0.010045

Device Test: 17.2 PVIN_UVLO_FALL(UVLO|PVIN_FALL/PVIN/4.5/4.5/0/1000/4.5/100kHz//@PVIN_UVLO_FALL)

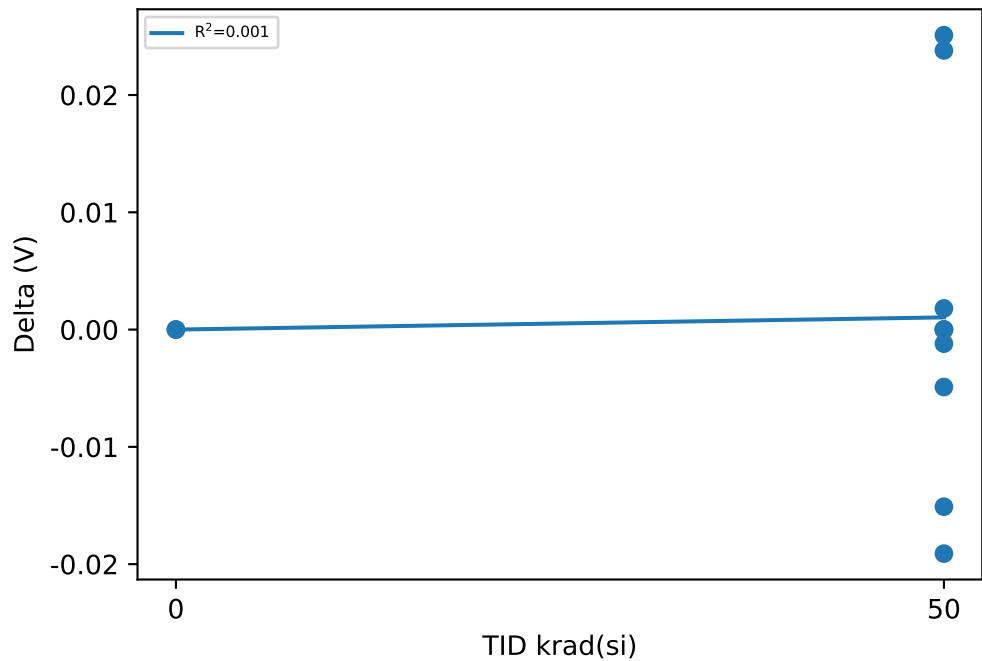
TID vs Result Stats



Test Results (Lower Limit = 3.45, Upper Limit = 3.75 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.572	3.572	0
2	0	Correlation	3.5671	3.5671	0
4	50	Bias	3.551	3.5461	-0.0049
6	50	Bias	3.556	3.556	0
7	50	Bias	3.572	3.5569	-0.0151
8	50	Bias	3.5659	3.5659	0
9	50	Bias	3.5751	3.556	-0.0191
11	50	Unbias	3.5711	3.5699	-0.0012
12	50	Unbias	3.5779	3.5779	0
13	50	Unbias	3.5581	3.5819	0.0238
14	50	Unbias	3.5591	3.5609	0.0018
15	50	Unbias	3.5779	3.603	0.0251

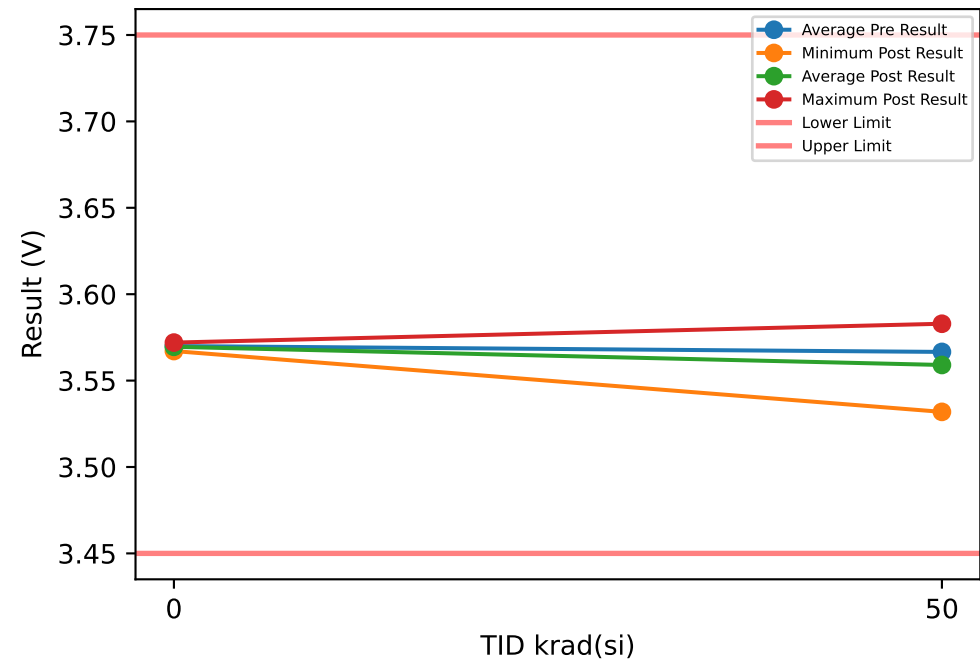
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5671	3.5696	3.572	0.0034648	3.5671	3.5696	3.572	0.0034648	0	0	0	0
50	3.551	3.5664	3.5779	0.0097831	3.5461	3.5675	3.603	0.016541	-0.0191	0.00104	0.0251	0.01417

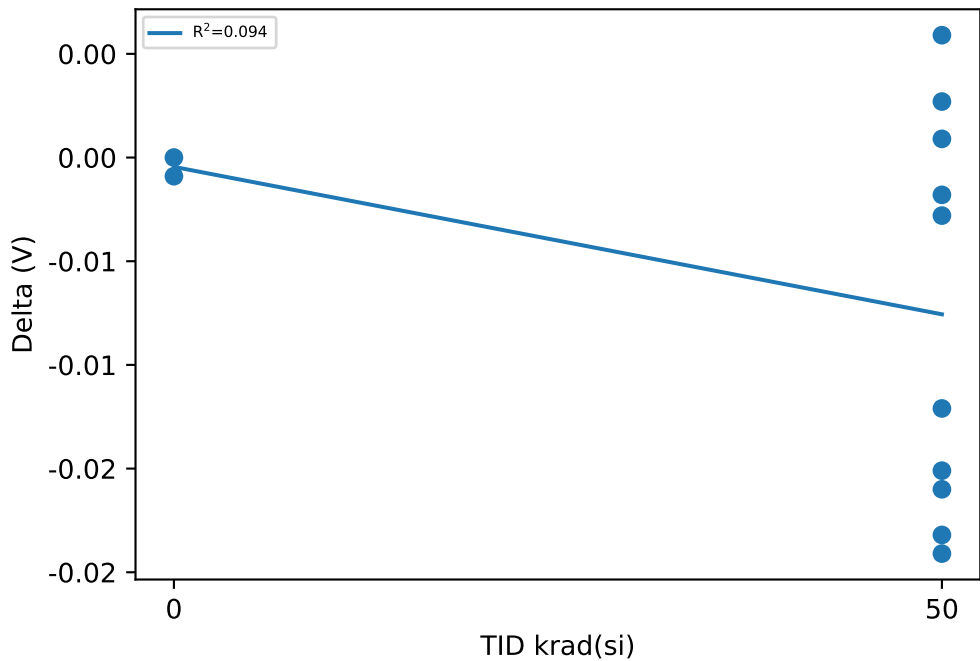
TID vs Result Stats



Test Results (Lower Limit = 3.45, Upper Limit = 3.75 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.572	3.572	0
2	0	Correlation	3.568	3.5671	-0.0009
4	50	Bias	3.5501	3.5319	-0.0182
6	50	Bias	3.556	3.5439	-0.0121
7	50	Bias	3.572	3.5569	-0.0151
8	50	Bias	3.5649	3.5489	-0.016
9	50	Bias	3.5751	3.556	-0.0191
11	50	Unbias	3.5739	3.5711	-0.0028
12	50	Unbias	3.5788	3.577	-0.0018
13	50	Unbias	3.5591	3.5618	0.0027
14	50	Unbias	3.5591	3.56	0.0009
15	50	Unbias	3.577	3.5829	0.0059

TID vs Post - Pre Exposure Delta

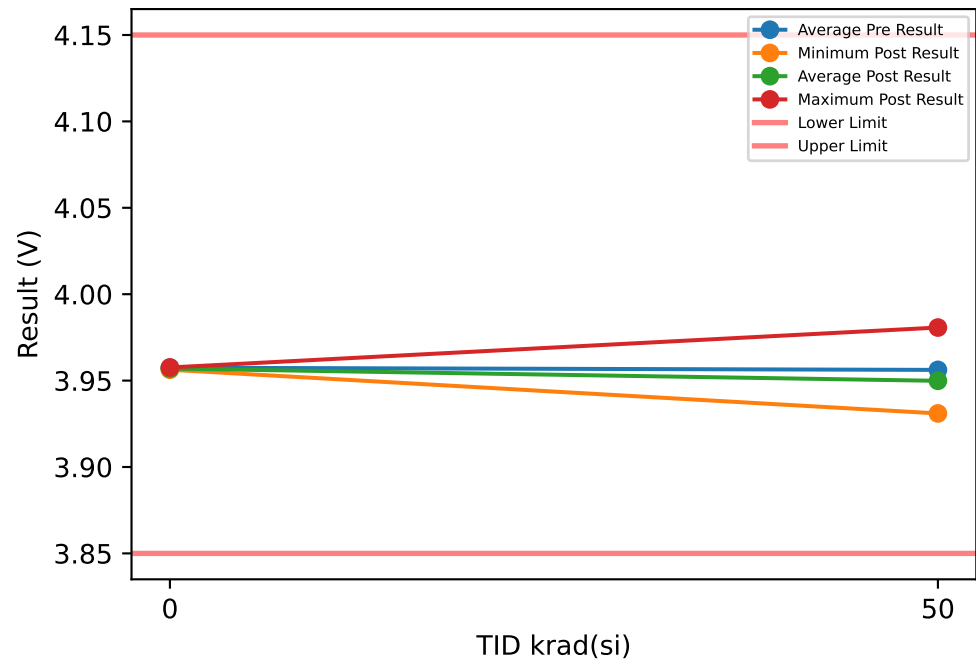


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.568	3.57	3.572	0.0028284	3.5671	3.5696	3.572	0.0034648	-0.0009	-0.00045	0	0.0006364
50	3.5501	3.5666	3.5788	0.010065	3.5319	3.559	3.5829	0.015378	-0.0191	-0.00756	0.0059	0.0094805

Device Test: 17.22 VIN_UVLO_RISE(UVLO|VIN_RISE/VIN/4.5/4.5/0/1000/4.5/1MHz//@VIN_UVLO_RISE)

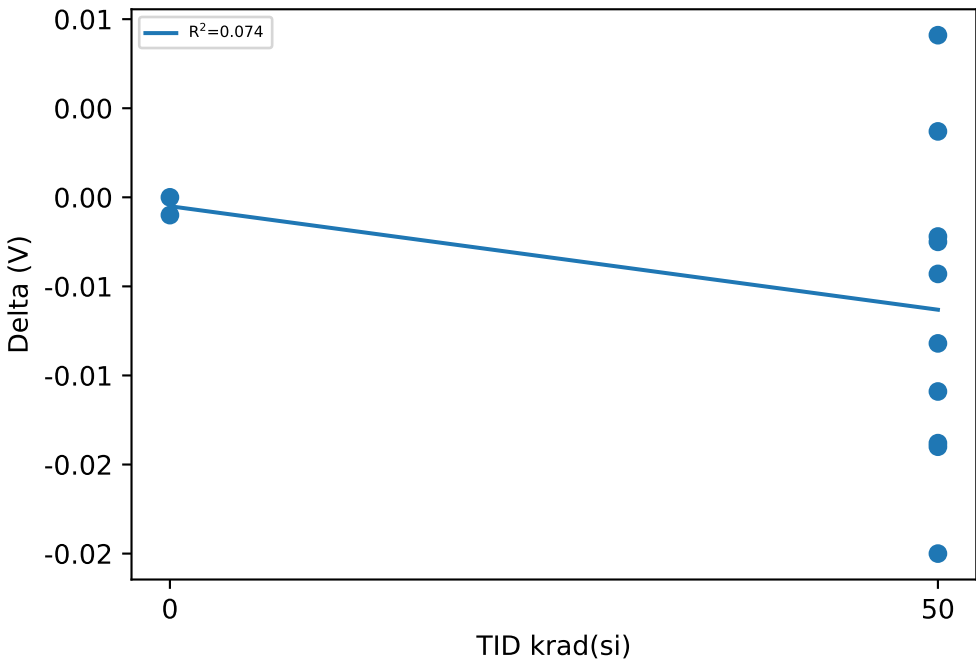
TID vs Result Stats



Test Results (Lower Limit = 3.85, Upper Limit = 4.15 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.9576	3.9576	0
2	0	Correlation	3.9573	3.9563	-0.001
4	50	Bias	3.951	3.931	-0.02
6	50	Bias	3.9473	3.9391	-0.0082
7	50	Bias	3.9485	3.9345	-0.014
8	50	Bias	3.9516	3.9407	-0.0109
9	50	Bias	3.9598	3.946	-0.0138
11	50	Unbias	3.9716	3.9807	0.0091
12	50	Unbias	3.9566	3.9541	-0.0025
13	50	Unbias	3.9538	3.9516	-0.0022
14	50	Unbias	3.9566	3.9523	-0.0043
15	50	Unbias	3.9651	3.9688	0.0037

TID vs Post - Pre Exposure Delta

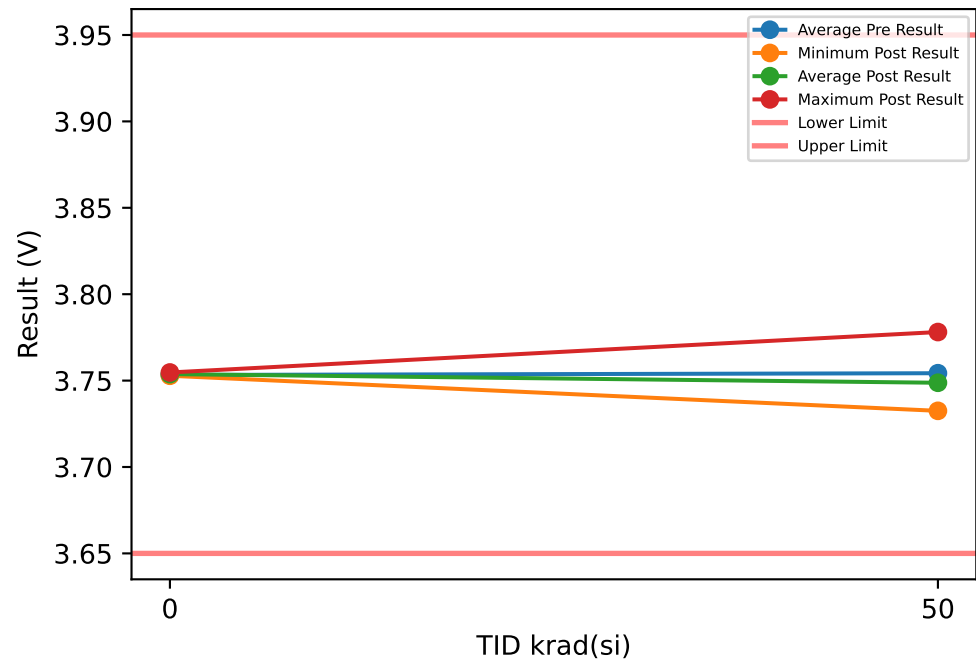


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.9573	3.9574	3.9576	0.00021213	3.9563	3.9569	3.9576	0.00091924	-0.001	-0.0005	0	0.00070711
50	3.9473	3.9562	3.9716	0.0076166	3.931	3.9499	3.9807	0.015431	-0.02	-0.00631	0.0091	0.0088217

Device Test: 17.23 VIN_UVLO_FALL(UVLO|VIN_FALL/VIN/4.5/4.5/0/1000/4.5/1MHz//@VIN_UVLO_FALL)

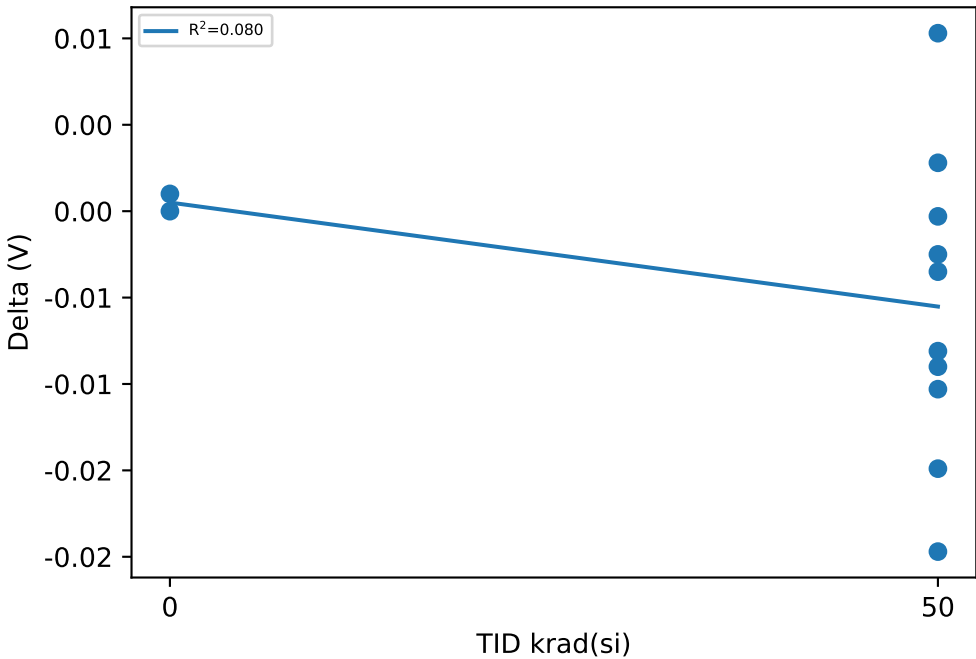
TID vs Result Stats



Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

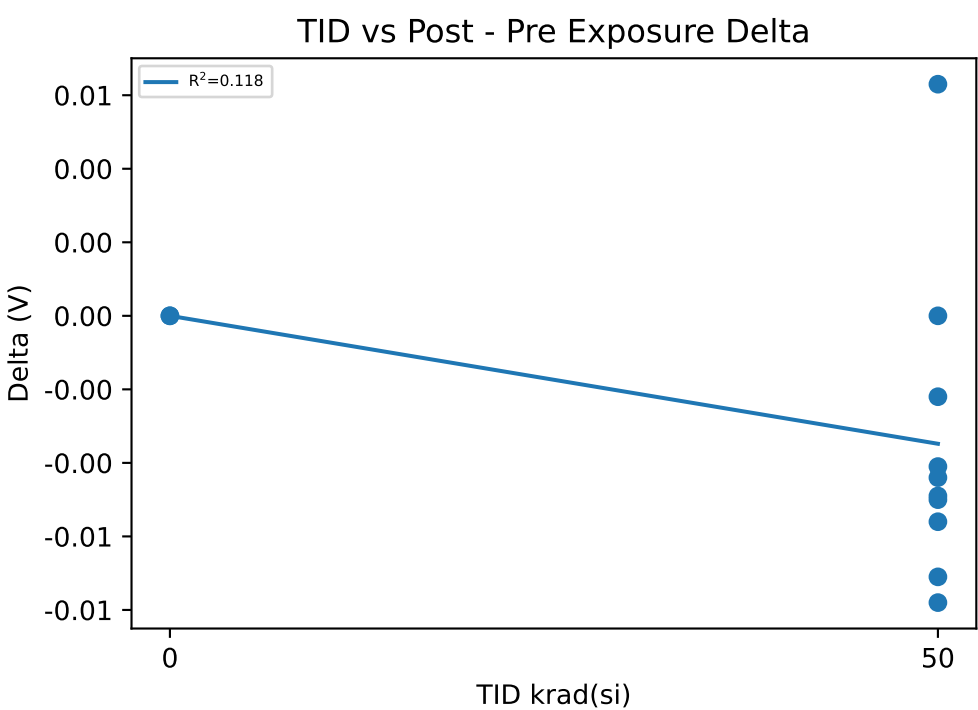
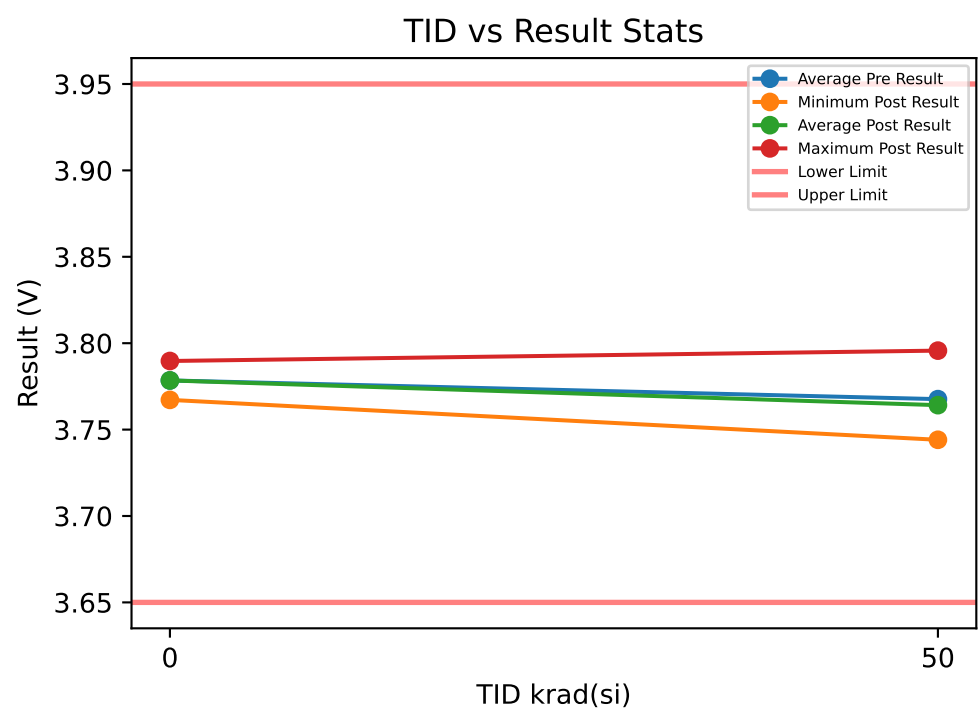
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.7537	3.7547	0.001
2	0	Correlation	3.7528	3.7528	0
4	50	Bias	3.7522	3.7325	-0.0197
6	50	Bias	3.7472	3.7369	-0.0103
7	50	Bias	3.7487	3.7338	-0.0149
8	50	Bias	3.7506	3.7416	-0.009
9	50	Bias	3.7537	3.7456	-0.0081
11	50	Unbias	3.7678	3.7781	0.0103
12	50	Unbias	3.7531	3.7528	-0.0003
13	50	Unbias	3.7522	3.7497	-0.0025
14	50	Unbias	3.7572	3.7537	-0.0035
15	50	Unbias	3.76	3.7628	0.0028

TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7528	3.7532	3.7537	0.0006364	3.7528	3.7538	3.7547	0.0013435	0	0.0005	0.001	0.00070711
50	3.7472	3.7543	3.7678	0.0060481	3.7325	3.7487	3.7781	0.014101	-0.0197	-0.00552	0.0103	0.0087599

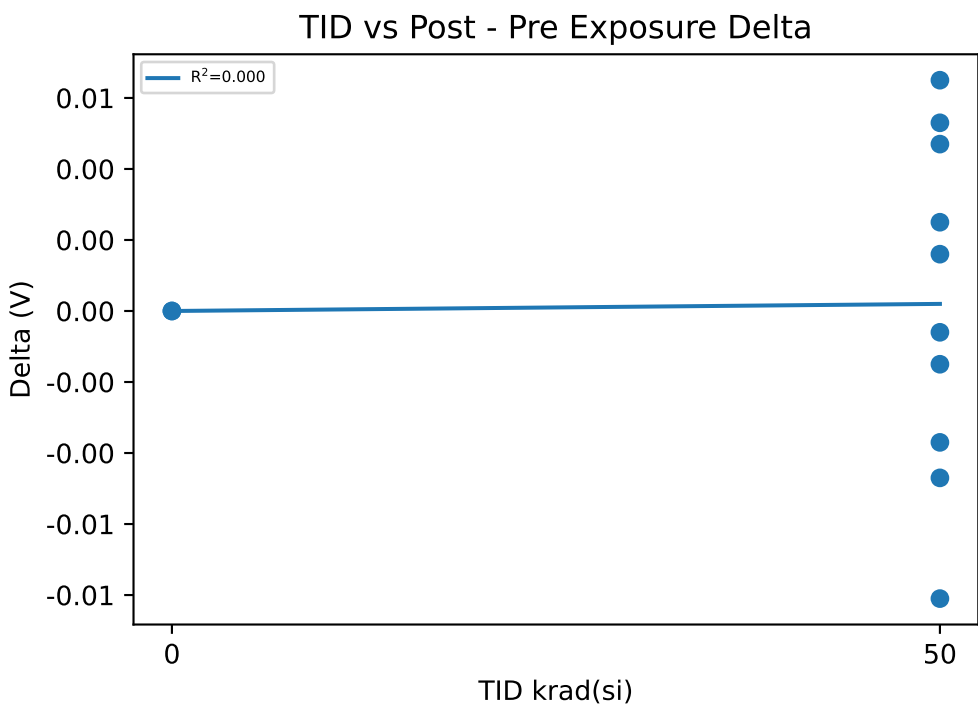
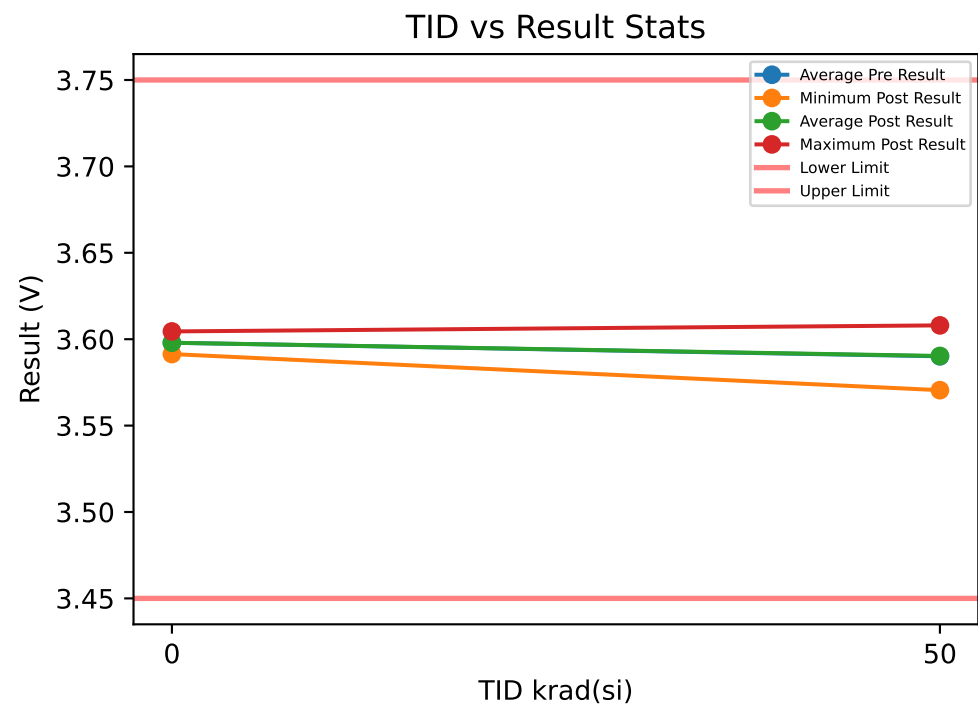


Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.7672	3.7672	0
2	0	Correlation	3.7897	3.7897	0
4	50	Bias	3.7597	3.7548	-0.0049
6	50	Bias	3.771	3.7669	-0.0041
7	50	Bias	3.7669	3.7613	-0.0056
8	50	Bias	3.7485	3.7441	-0.0044
9	50	Bias	3.7566	3.7516	-0.005
11	50	Unbias	3.7894	3.7957	0.0063
12	50	Unbias	3.7797	3.7775	-0.0022
13	50	Unbias	3.771	3.7632	-0.0078
14	50	Unbias	3.7697	3.7626	-0.0071
15	50	Unbias	3.7638	3.7638	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7672	3.7784	3.7897	0.01591	3.7672	3.7784	3.7897	0.01591	0	0	0	0
50	3.7485	3.7676	3.7894	0.011606	3.7441	3.7641	3.7957	0.014297	-0.0078	-0.00348	0.0063	0.004099



Test Results (Lower Limit = 3.45, Upper Limit = 3.75 (V))

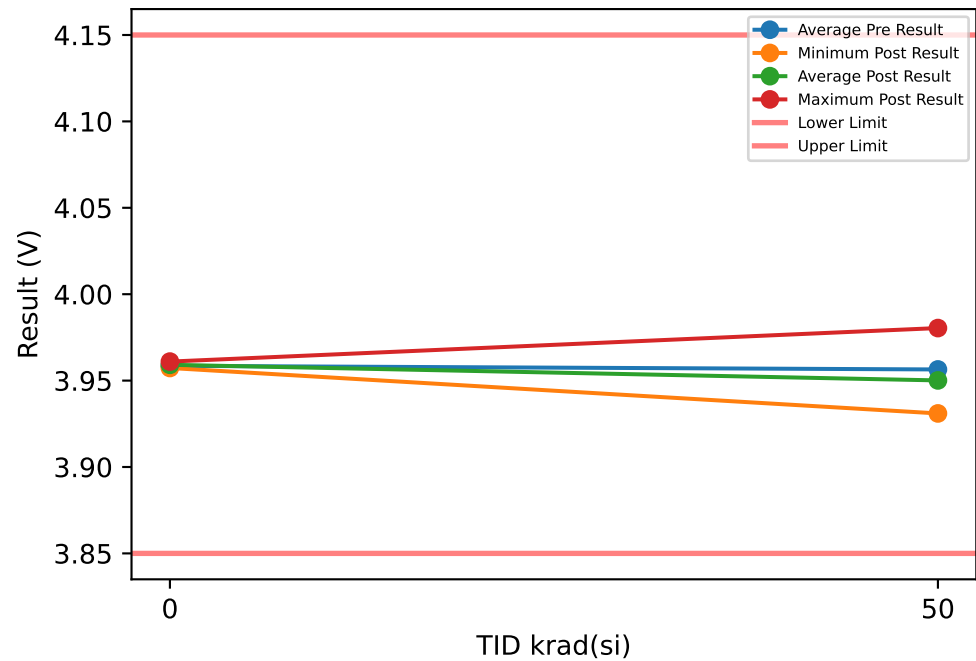
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.5914	3.5914	0
2	0	Correlation	3.6045	3.6045	0
4	50	Bias	3.5942	3.5927	-0.0015
6	50	Bias	3.5799	3.5864	0.0065
7	50	Bias	3.5805	3.5799	-0.0006
8	50	Bias	3.5786	3.5705	-0.0081
9	50	Bias	3.5874	3.5827	-0.0047
11	50	Unbias	3.6117	3.608	-0.0037
12	50	Unbias	3.5995	3.6042	0.0047
13	50	Unbias	3.597	3.5986	0.0016
14	50	Unbias	3.5864	3.5917	0.0053
15	50	Unbias	3.5858	3.5883	0.0025

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5914	3.5979	3.6045	0.0092631	3.5914	3.5979	3.6045	0.0092631	0	0	0	0
50	3.5786	3.5901	3.6117	0.010474	3.5705	3.5903	3.608	0.011354	-0.0081	0.0002	0.0065	0.0047707

Device Test: 17.4 VIN_UVLO_RISE(UVLO|VIN_RISE/VIN/4.5/4.5/0/1000/4.5/100kHz//@VIN_UVLO_RISE)

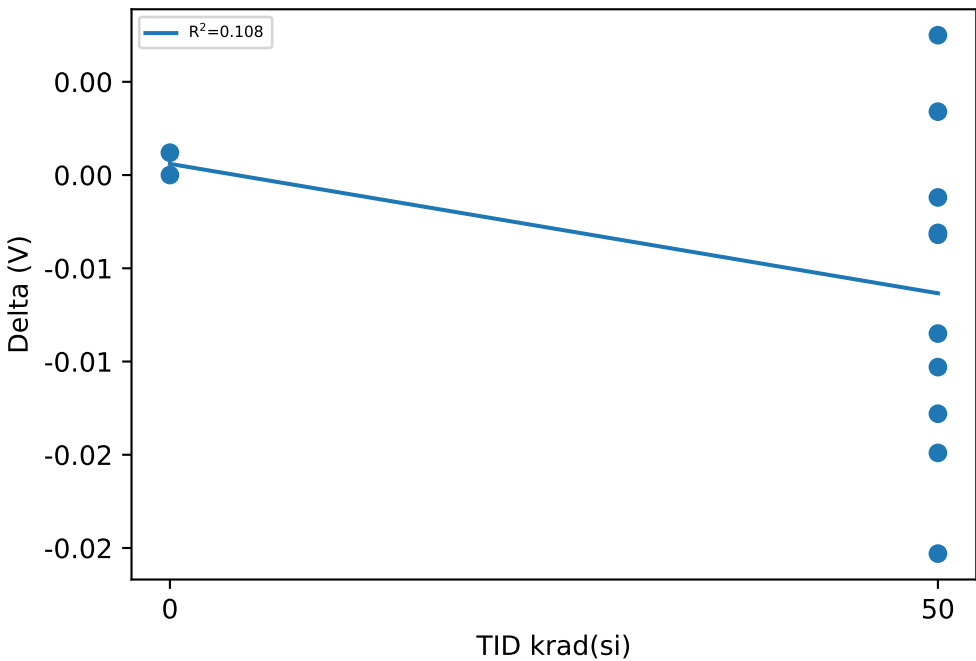
TID vs Result Stats



Test Results (Lower Limit = 3.85, Upper Limit = 4.15 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.9573	3.9573	0
2	0	Correlation	3.9598	3.961	0.0012
4	50	Bias	3.9513	3.931	-0.0203
6	50	Bias	3.9473	3.9388	-0.0085
7	50	Bias	3.9491	3.9342	-0.0149
8	50	Bias	3.9513	3.941	-0.0103
9	50	Bias	3.9598	3.947	-0.0128
11	50	Unbias	3.9729	3.9804	0.0075
12	50	Unbias	3.9563	3.9551	-0.0012
13	50	Unbias	3.9548	3.9516	-0.0032
14	50	Unbias	3.9563	3.9532	-0.0031
15	50	Unbias	3.9654	3.9688	0.0034

TID vs Post - Pre Exposure Delta

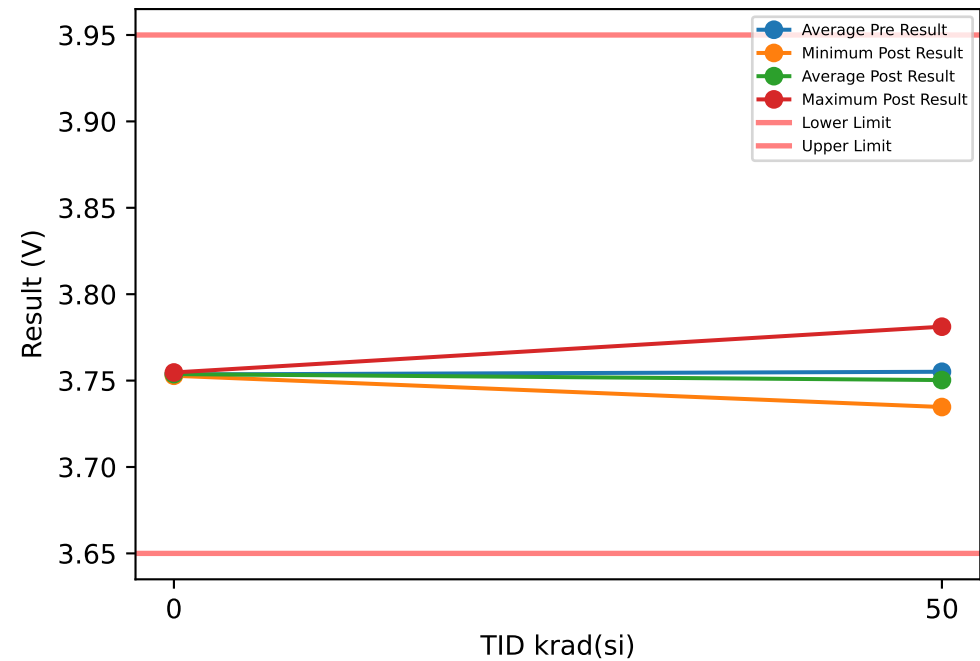


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.9573	3.9585	3.9598	0.0017678	3.9573	3.9592	3.961	0.0026163	0	0.0006	0.0012	0.00084853
50	3.9473	3.9565	3.9729	0.0078562	3.931	3.9501	3.9804	0.015429	-0.0203	-0.00634	0.0075	0.0085857

Device Test: 17.5 VIN_UVLO_FALL(UVLO|VIN_FALL/VIN/4.5/4.5/0/1000/4.5/100kHz//@VIN_UVLO_FALL)

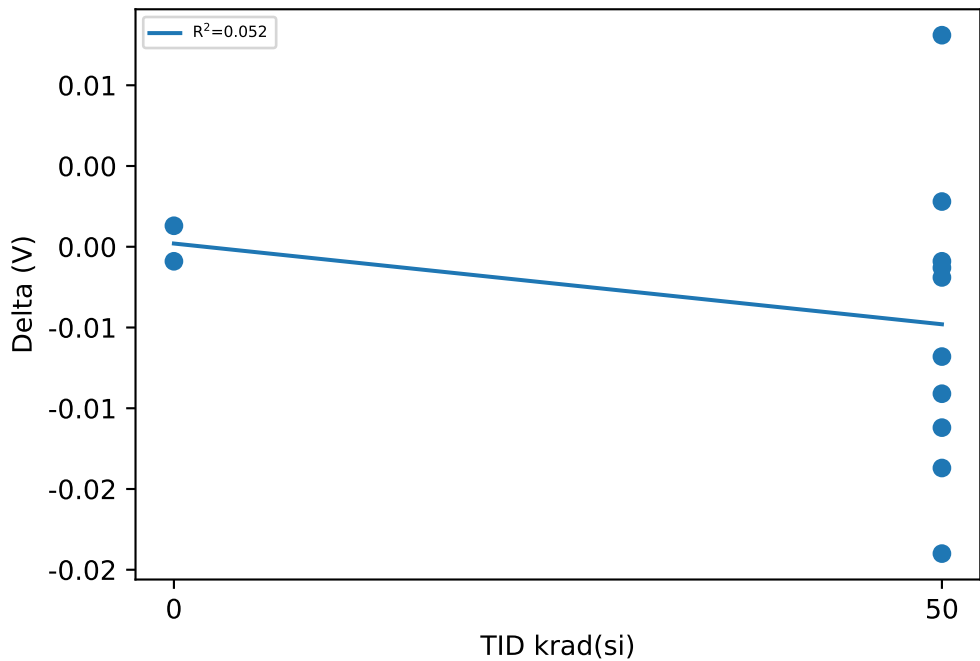
TID vs Result Stats



Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

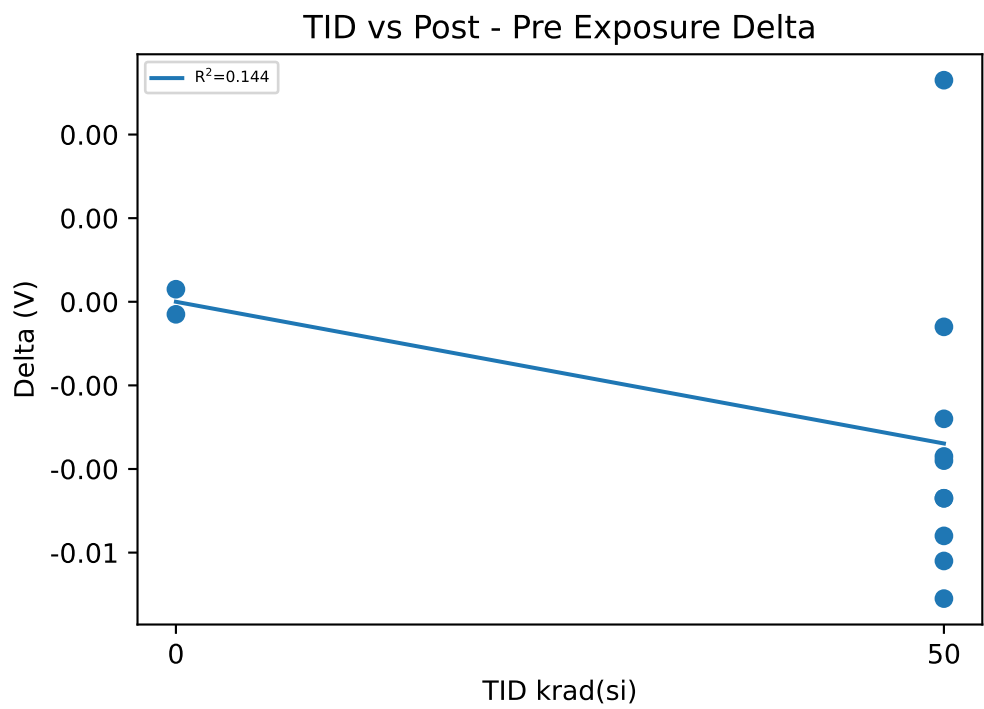
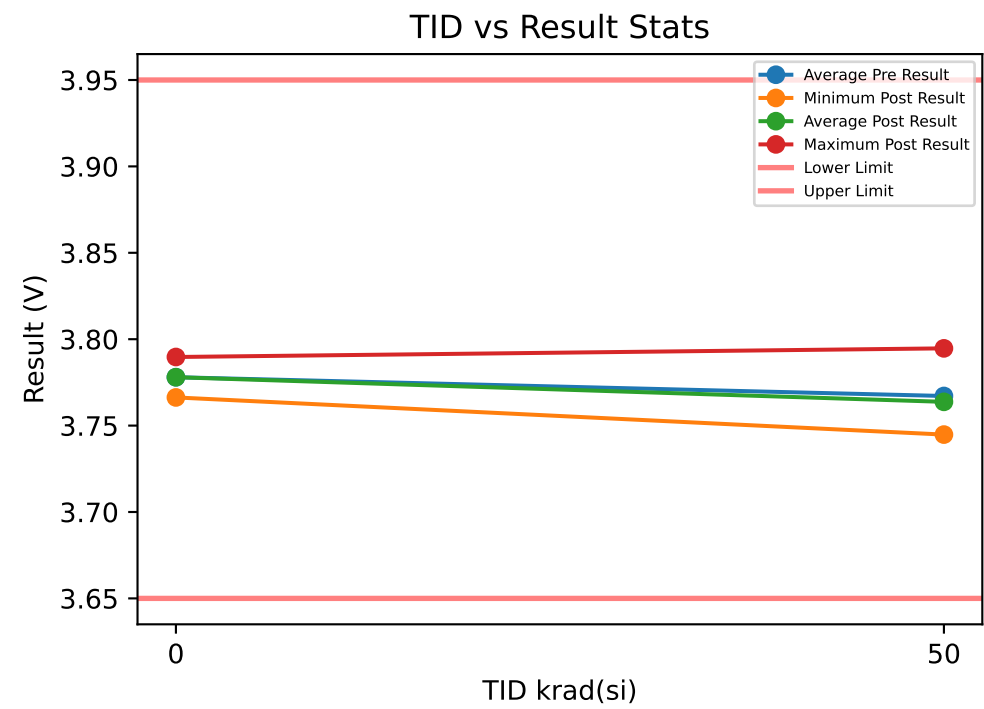
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.7534	3.7547	0.0013
2	0	Correlation	3.7537	3.7528	-0.0009
4	50	Bias	3.7537	3.7347	-0.019
6	50	Bias	3.7481	3.7369	-0.0112
7	50	Bias	3.7497	3.736	-0.0137
8	50	Bias	3.7519	3.7428	-0.0091
9	50	Bias	3.7537	3.7469	-0.0068
11	50	Unbias	3.7681	3.7812	0.0131
12	50	Unbias	3.755	3.7541	-0.0009
13	50	Unbias	3.7522	3.7509	-0.0013
14	50	Unbias	3.7578	3.7559	-0.0019
15	50	Unbias	3.7609	3.7637	0.0028

TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7534	3.7535	3.7537	0.00021213	3.7528	3.7538	3.7547	0.0013435	-0.0009	0.0002	0.0013	0.0015556
50	3.7481	3.7551	3.7681	0.0058753	3.7347	3.7503	3.7812	0.014437	-0.019	-0.0048	0.0131	0.0091793



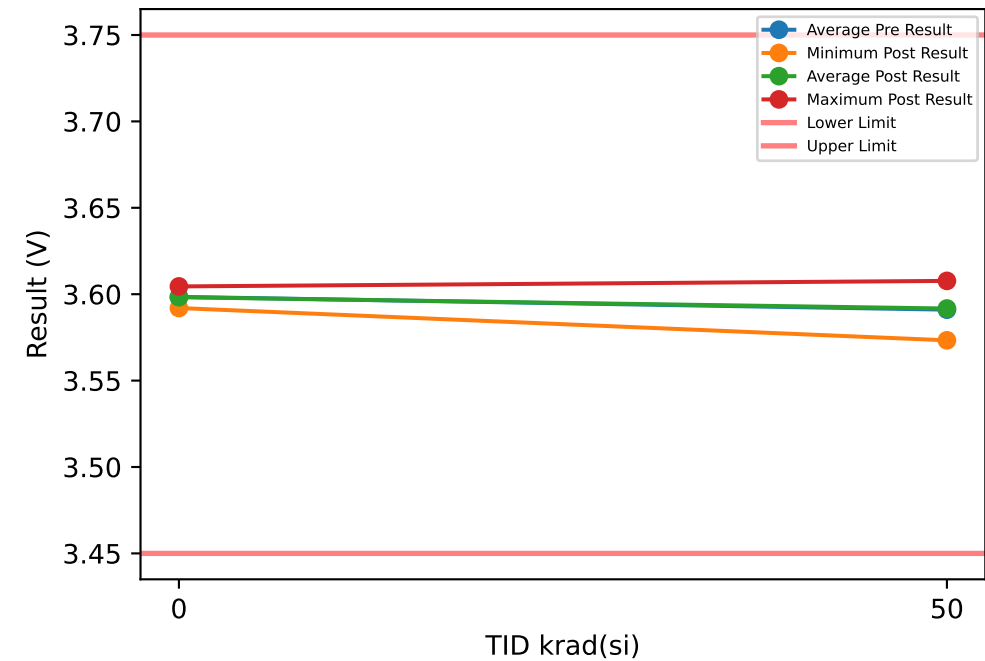
Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.7666	3.7663	-0.0003
2	0	Correlation	3.7894	3.7897	0.0003
4	50	Bias	3.7585	3.7538	-0.0047
6	50	Bias	3.7701	3.7663	-0.0038
7	50	Bias	3.766	3.7613	-0.0047
8	50	Bias	3.7485	3.7448	-0.0037
9	50	Bias	3.7566	3.751	-0.0056
11	50	Unbias	3.7894	3.7947	0.0053
12	50	Unbias	3.7797	3.7769	-0.0028
13	50	Unbias	3.7697	3.7635	-0.0062
14	50	Unbias	3.7697	3.7626	-0.0071
15	50	Unbias	3.7632	3.7626	-0.0006

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7666	3.778	3.7894	0.016122	3.7663	3.778	3.7897	0.016546	-0.0003	0	0.0003	0.00042426
50	3.7485	3.7671	3.7894	0.011667	3.7448	3.7638	3.7947	0.014011	-0.0071	-0.00339	0.0053	0.0035573

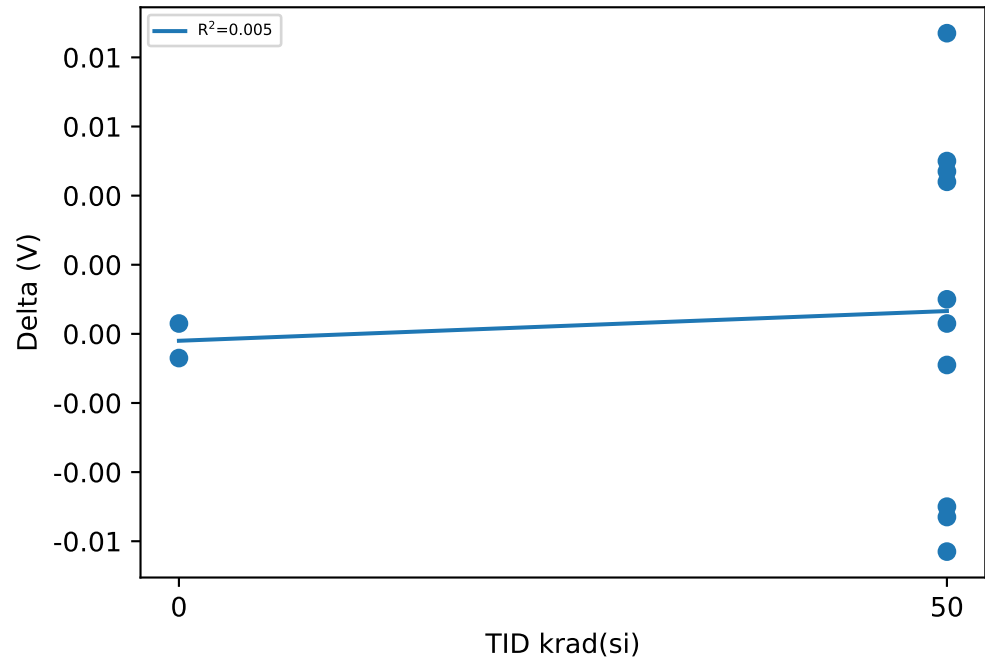
TID vs Result Stats



Test Results (Lower Limit = 3.45, Upper Limit = 3.75 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.5927	3.592	-0.0007
2	0	Correlation	3.6042	3.6045	0.0003
4	50	Bias	3.5942	3.5945	0.0003
6	50	Bias	3.5799	3.5886	0.0087
7	50	Bias	3.5805	3.5796	-0.0009
8	50	Bias	3.5796	3.5733	-0.0063
9	50	Bias	3.5889	3.5836	-0.0053
11	50	Unbias	3.6127	3.6077	-0.005
12	50	Unbias	3.6005	3.6055	0.005
13	50	Unbias	3.5995	3.6005	0.001
14	50	Unbias	3.5883	3.593	0.0047
15	50	Unbias	3.5864	3.5908	0.0044

TID vs Post - Pre Exposure Delta

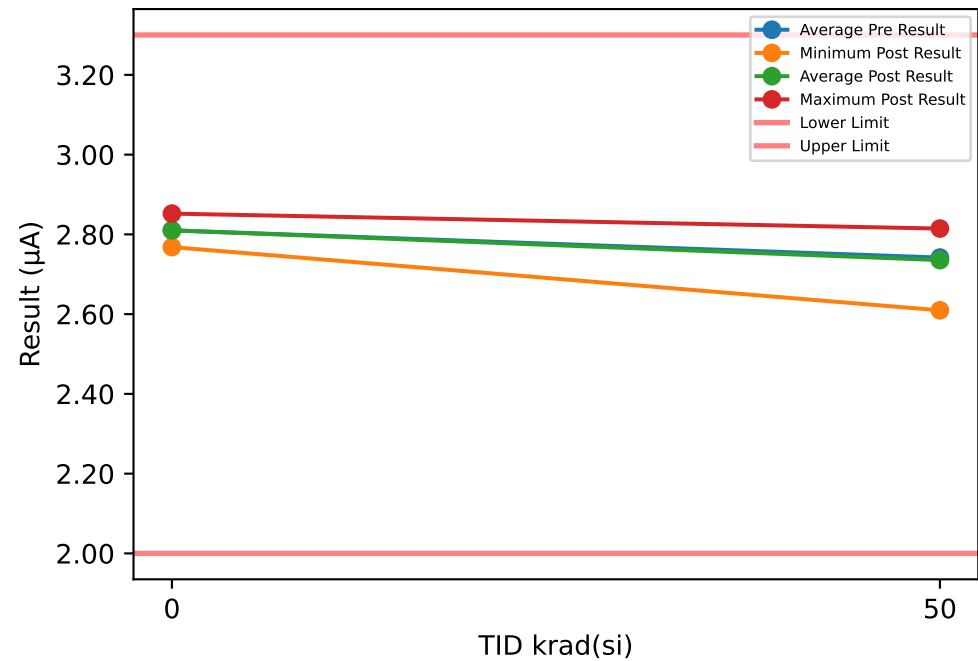


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5927	3.5984	3.6042	0.0081317	3.592	3.5983	3.6045	0.0088388	-0.0007	-0.0002	0.0003	0.00070711
50	3.5796	3.5911	3.6127	0.010749	3.5733	3.5917	3.6077	0.011027	-0.0063	0.00066	0.0087	0.0050823

Device Test: 18.1 I_SS(CURRENT|SS_0p3V/SS/4.5/4.5/0/1000/4.5/100kHz//@I_SS)

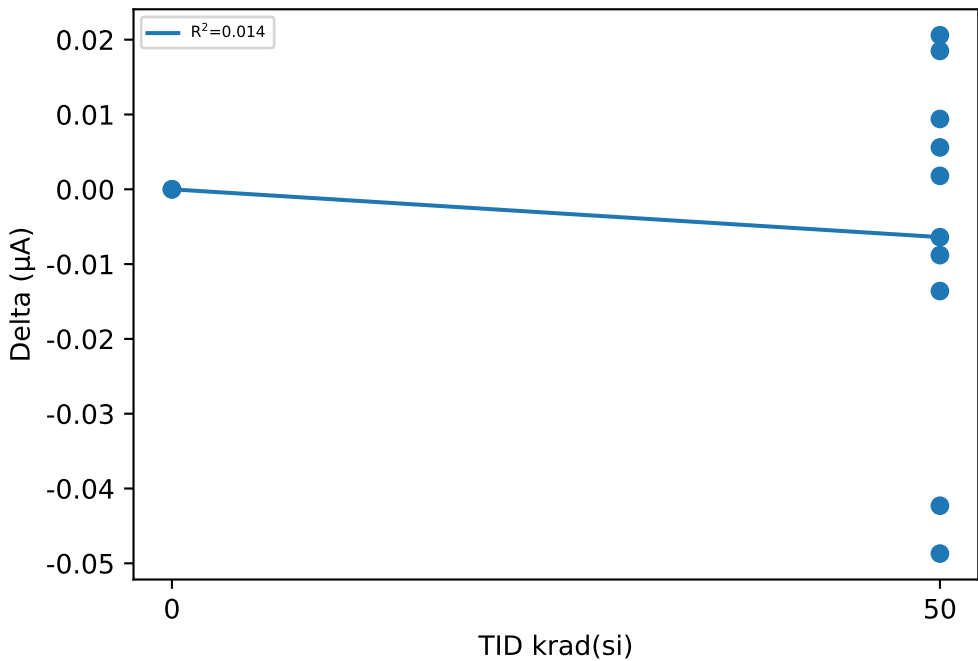
TID vs Result Stats



Test Results (Lower Limit = 2.0, Upper Limit = 3.3 (µA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	2.8521	2.8521	0
2	0	Correlation	2.7682	2.7682	0
4	50	Bias	2.736	2.7545	0.0185
6	50	Bias	2.7261	2.6838	-0.0423
7	50	Bias	2.7968	2.788	-0.0088
8	50	Bias	2.755	2.7644	0.0094
9	50	Bias	2.7592	2.7456	-0.0136
11	50	Unbias	2.7311	2.7247	-0.0064
12	50	Unbias	2.6583	2.6096	-0.0487
13	50	Unbias	2.6746	2.6802	0.0056
14	50	Unbias	2.7878	2.7896	0.0018
15	50	Unbias	2.794	2.8146	0.0206

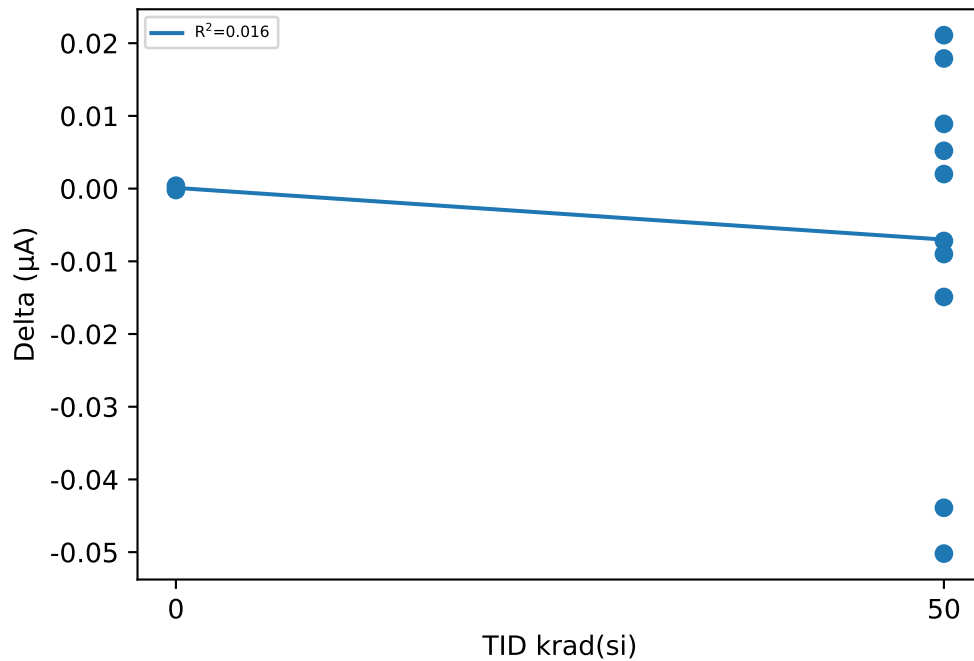
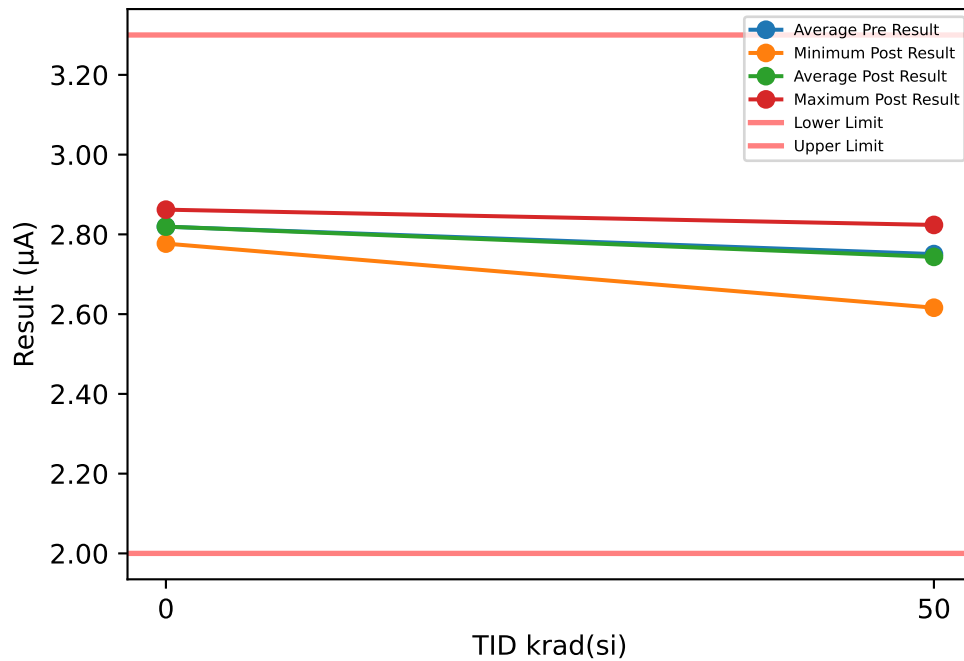
TID vs Post - Pre Exposure Delta



Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.7682	2.8102	2.8521	0.059326	2.7682	2.8102	2.8521	0.059326	0	0	0	0
50	2.6583	2.7419	2.7968	0.047405	2.6096	2.7355	2.8146	0.062304	-0.0487	-0.00639	0.0206	0.023442

Device Test: 18.13 |_SS(CURRENT|SS_0p3V/SS/14/14/0/1000/5/100kHz//@|_SS)



Test Results (Lower Limit = 2.0,
Upper Limit = 3.3 (μA))

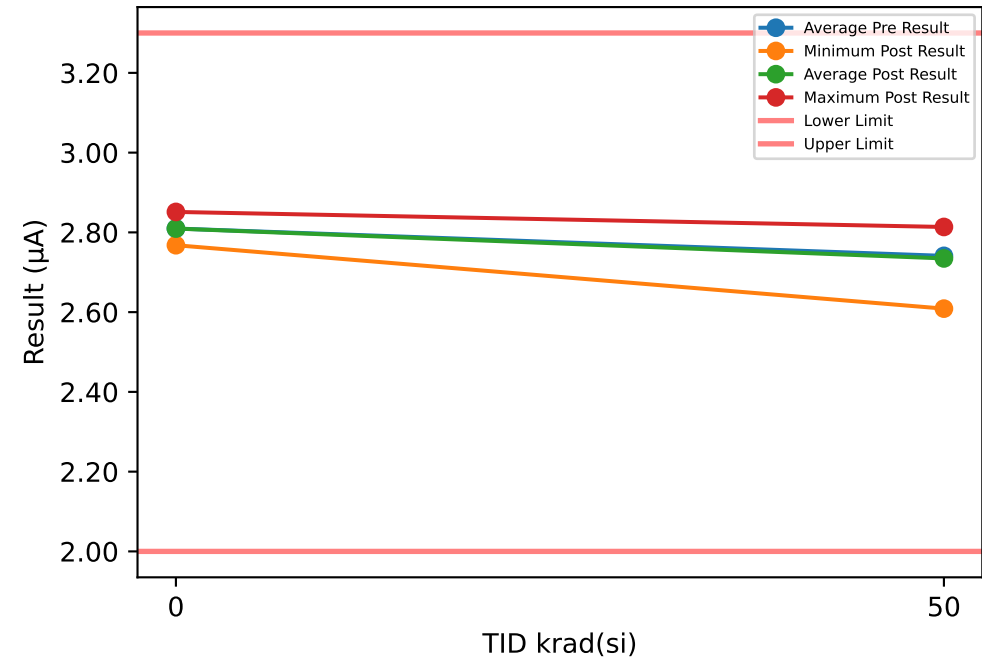
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	2.8616	2.862	0.0004
2	0	Correlation	2.7771	2.7769	-0.0002
4	50	Bias	2.7449	2.7628	0.0179
6	50	Bias	2.7356	2.6917	-0.0439
7	50	Bias	2.806	2.797	-0.009
8	50	Bias	2.7639	2.7728	0.0089
9	50	Bias	2.7682	2.7533	-0.0149
11	50	Unbias	2.7394	2.7322	-0.0072
12	50	Unbias	2.6663	2.6161	-0.0502
13	50	Unbias	2.6828	2.688	0.0052
14	50	Unbias	2.7961	2.7981	0.002
15	50	Unbias	2.8026	2.8237	0.0211

Test Statistics (μA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.7771	2.8194	2.8616	0.059751	2.7769	2.8194	2.862	0.060175	-0.0002	0.0001	0.0004	0.00042426
50	2.6663	2.7506	2.806	0.047629	2.6161	2.7436	2.8237	0.063003	-0.0502	-0.00701	0.0211	0.024006

Device Test: 18.17 I_SS(CURRENT|SS_0p3V/SS/4.5/4.5/0/1000/4.5/500kHz//@I_SS)

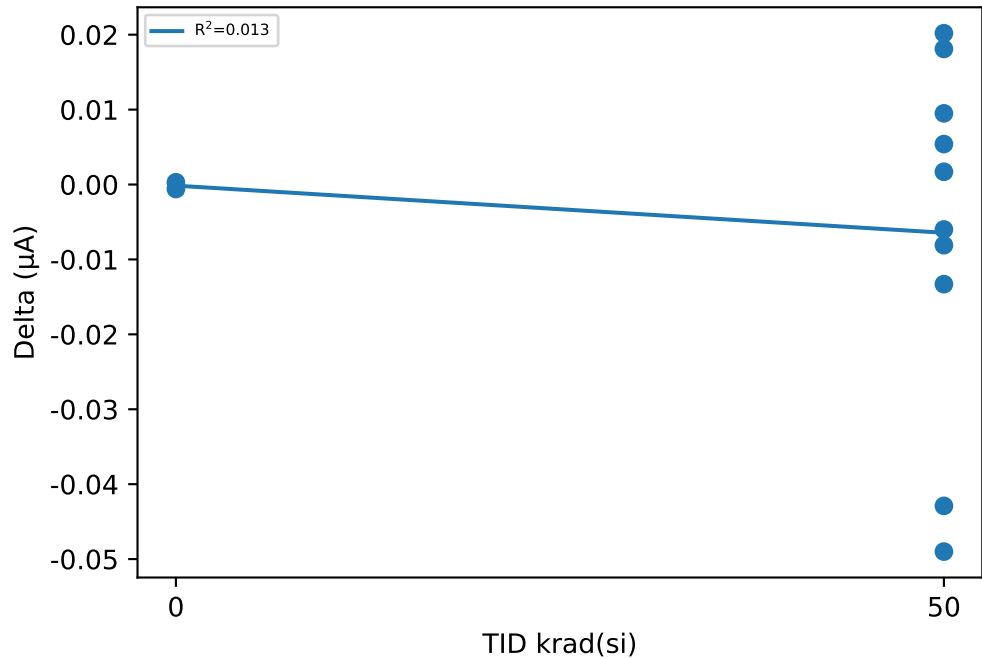
TID vs Result Stats



Test Results (Lower Limit = 2.0, Upper Limit = 3.3 (µA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	2.8519	2.8513	-0.0006
2	0	Correlation	2.7675	2.7678	0.0003
4	50	Bias	2.7353	2.7534	0.0181
6	50	Bias	2.7254	2.6825	-0.0429
7	50	Bias	2.7961	2.788	-0.0081
8	50	Bias	2.7541	2.7636	0.0095
9	50	Bias	2.7586	2.7453	-0.0133
11	50	Unbias	2.7302	2.7242	-0.006
12	50	Unbias	2.6578	2.6088	-0.049
13	50	Unbias	2.6738	2.6792	0.0054
14	50	Unbias	2.7865	2.7882	0.0017
15	50	Unbias	2.7934	2.8136	0.0202

TID vs Post - Pre Exposure Delta

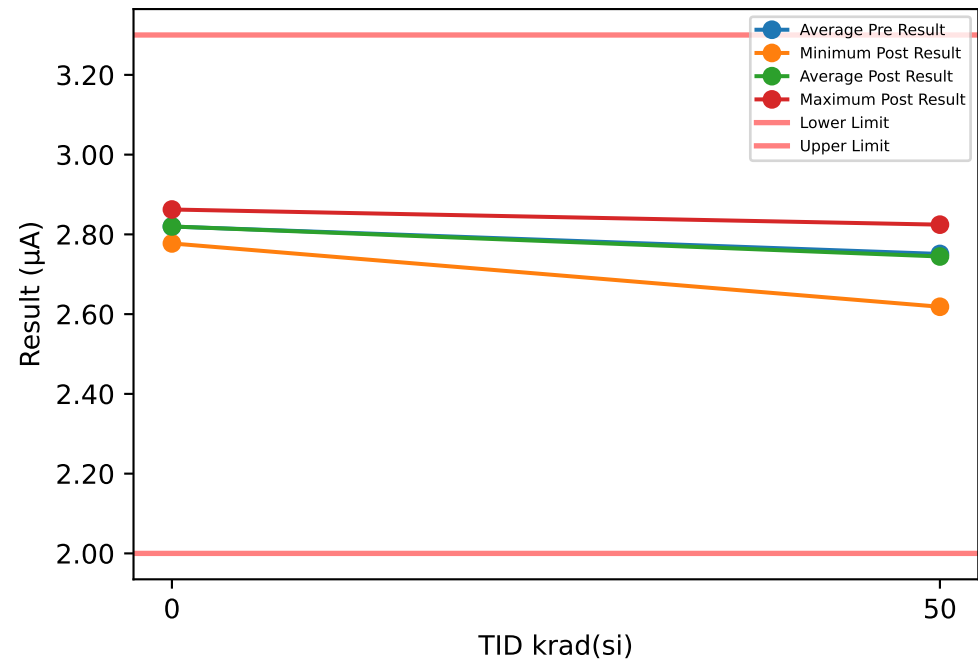


Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.7675	2.8097	2.8519	0.05968	2.7678	2.8095	2.8513	0.059043	-0.0006	-0.00015	0.0003	0.0006364
50	2.6578	2.7411	2.7961	0.047333	2.6088	2.7347	2.8136	0.062354	-0.049	-0.00644	0.0202	0.023483

Device Test: 18.21 I_SS(CURRENT|SS_0p3V/SS/5/5/0/1000/5/500kHz//@I_SS)

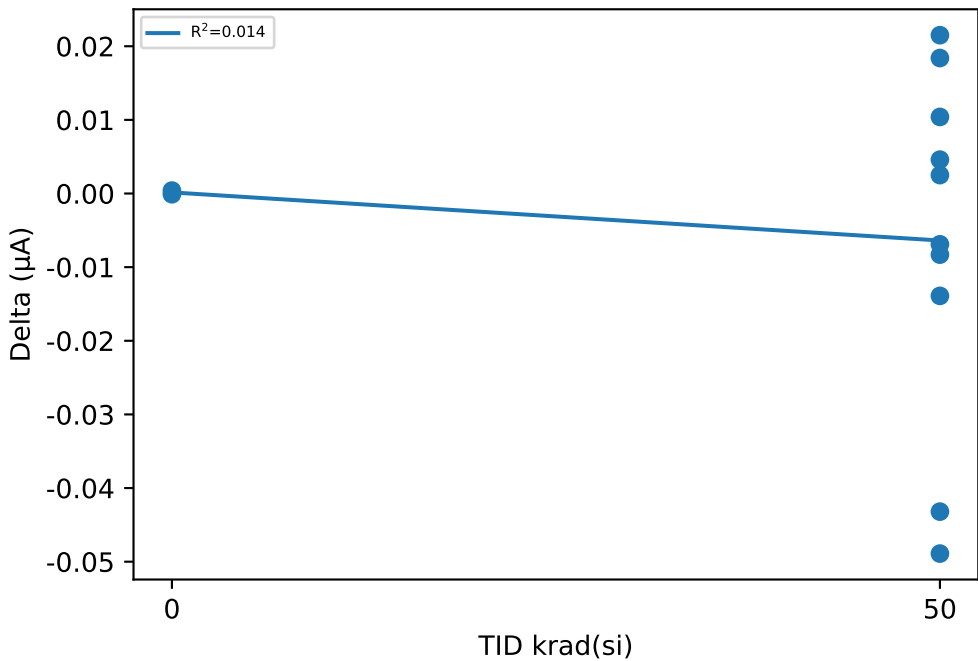
TID vs Result Stats



Test Results (Lower Limit = 2.0, Upper Limit = 3.3 (µA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	2.8625	2.8624	-0.0001
2	0	Correlation	2.7769	2.7773	0.0004
4	50	Bias	2.7447	2.7631	0.0184
6	50	Bias	2.7353	2.6921	-0.0432
7	50	Bias	2.8065	2.7982	-0.0083
8	50	Bias	2.7642	2.7746	0.0104
9	50	Bias	2.7683	2.7544	-0.0139
11	50	Unbias	2.7401	2.7332	-0.0069
12	50	Unbias	2.6674	2.6185	-0.0489
13	50	Unbias	2.6833	2.6879	0.0046
14	50	Unbias	2.7967	2.7992	0.0025
15	50	Unbias	2.8029	2.8244	0.0215

TID vs Post - Pre Exposure Delta

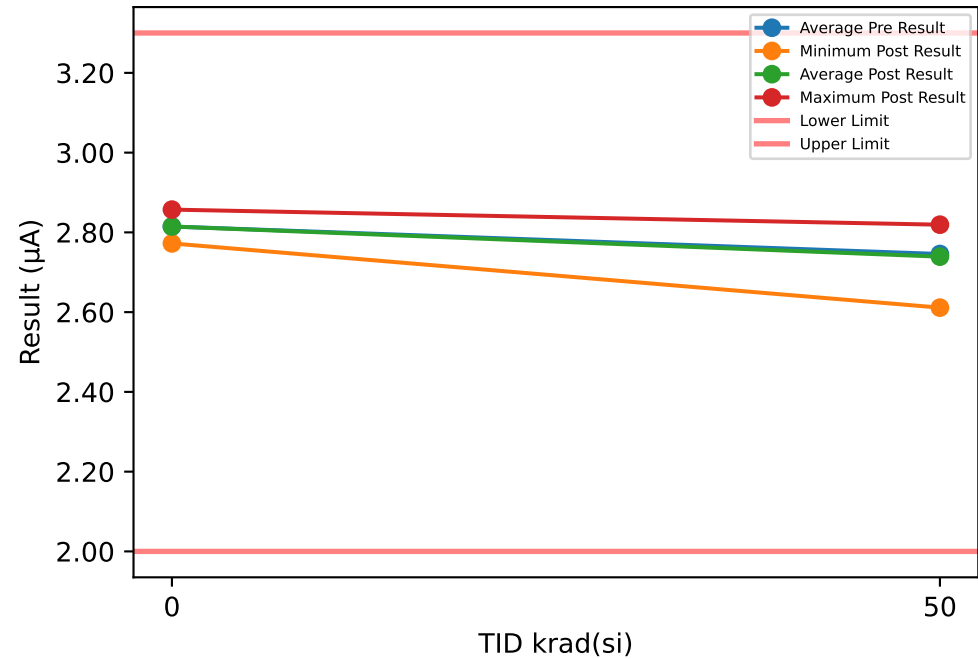


Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.7769	2.8197	2.8625	0.060528	2.7773	2.8198	2.8624	0.060175	-0.0001	0.00015	0.0004	0.00035355
50	2.6674	2.7509	2.8065	0.047508	2.6185	2.7446	2.8244	0.06286	-0.0489	-0.00638	0.0215	0.023797

Device Test: 18.25 I_SS(CURRENT|SS_0p3V/SS/12/12/0/1000/5/500kHz//@I_SS)

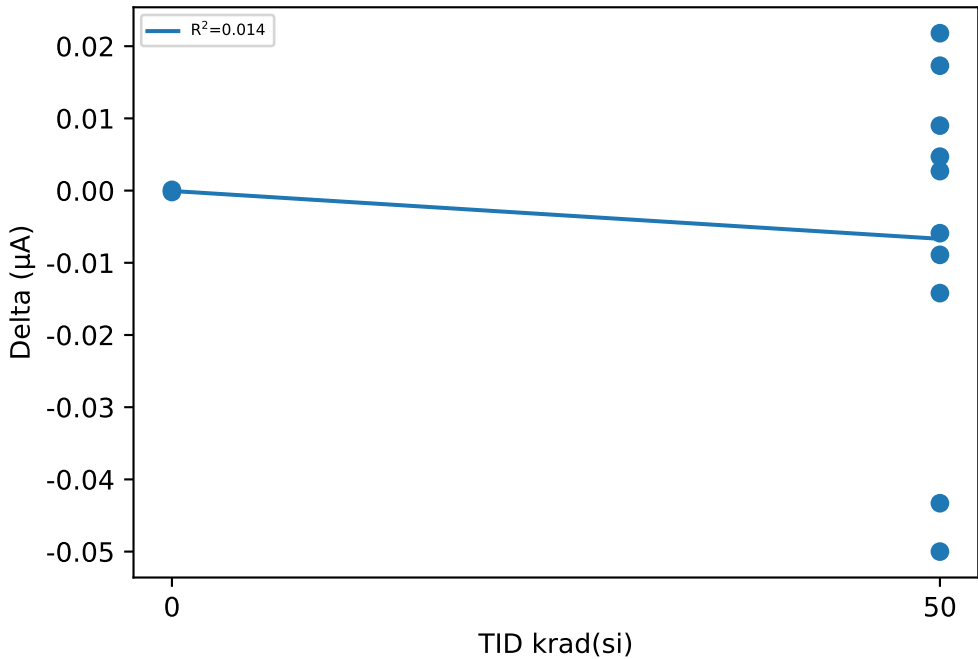
TID vs Result Stats



Test Results (Lower Limit = 2.0, Upper Limit = 3.3 (µA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	2.8573	2.8571	-0.0002
2	0	Correlation	2.7722	2.7723	0.0001
4	50	Bias	2.7403	2.7576	0.0173
6	50	Bias	2.7302	2.6869	-0.0433
7	50	Bias	2.8015	2.7926	-0.0089
8	50	Bias	2.7594	2.7684	0.009
9	50	Bias	2.7632	2.749	-0.0142
11	50	Unbias	2.735	2.7291	-0.0059
12	50	Unbias	2.6613	2.6113	-0.05
13	50	Unbias	2.6785	2.6832	0.0047
14	50	Unbias	2.7911	2.7938	0.0027
15	50	Unbias	2.7975	2.8193	0.0218

TID vs Post - Pre Exposure Delta

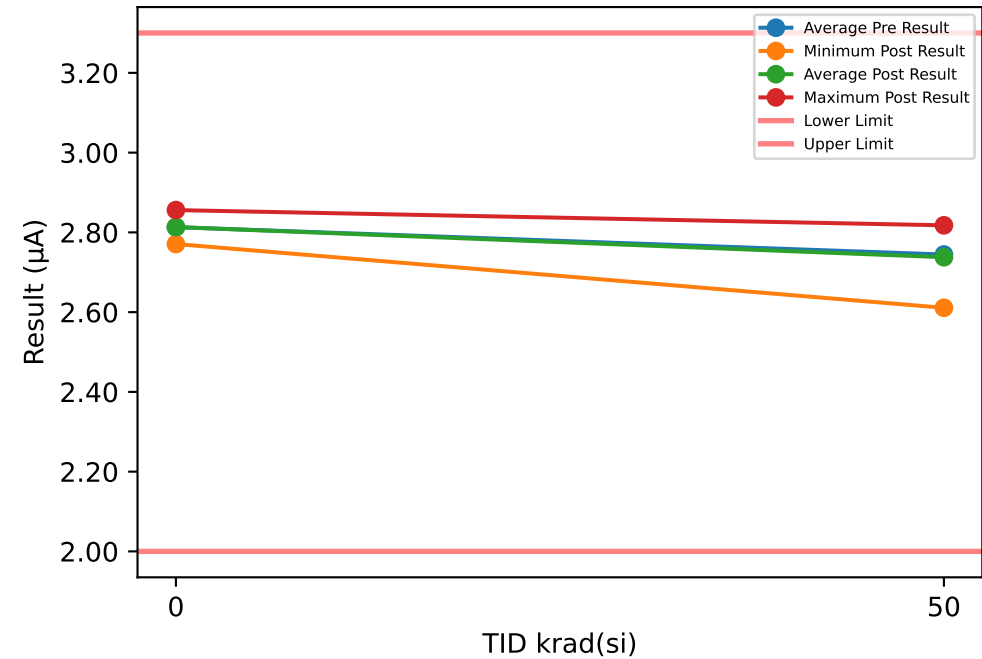


Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.7722	2.8148	2.8573	0.060175	2.7723	2.8147	2.8571	0.059963	-0.0002	-5e-05	0.0001	0.00021213
50	2.6613	2.7458	2.8015	0.04758	2.6113	2.7391	2.8193	0.063129	-0.05	-0.00668	0.0218	0.023873

Device Test: 18.29 I_SS(CURRENT|SS_0p3V/SS/14/14/0/1000/5/500kHz//@I_SS)

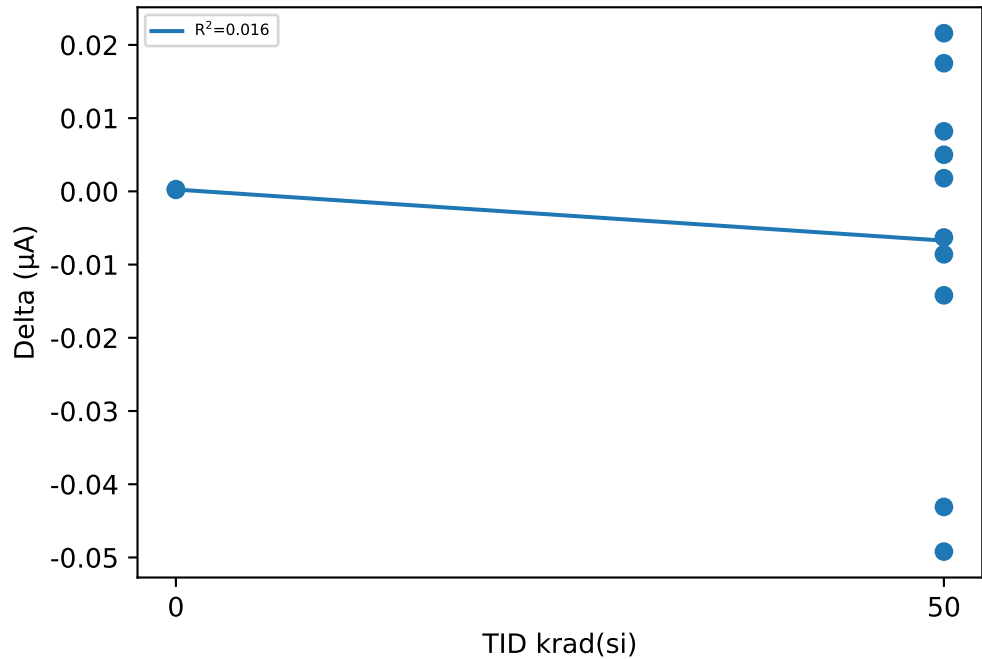
TID vs Result Stats



Test Results (Lower Limit = 2.0, Upper Limit = 3.3 (µA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	2.8556	2.8559	0.0003
2	0	Correlation	2.7706	2.7708	0.0002
4	50	Bias	2.7386	2.7561	0.0175
6	50	Bias	2.7291	2.686	-0.0431
7	50	Bias	2.8001	2.7915	-0.0086
8	50	Bias	2.7581	2.7663	0.0082
9	50	Bias	2.7619	2.7477	-0.0142
11	50	Unbias	2.7333	2.727	-0.0063
12	50	Unbias	2.6601	2.6109	-0.0492
13	50	Unbias	2.6771	2.6821	0.005
14	50	Unbias	2.7902	2.792	0.0018
15	50	Unbias	2.7961	2.8177	0.0216

TID vs Post - Pre Exposure Delta

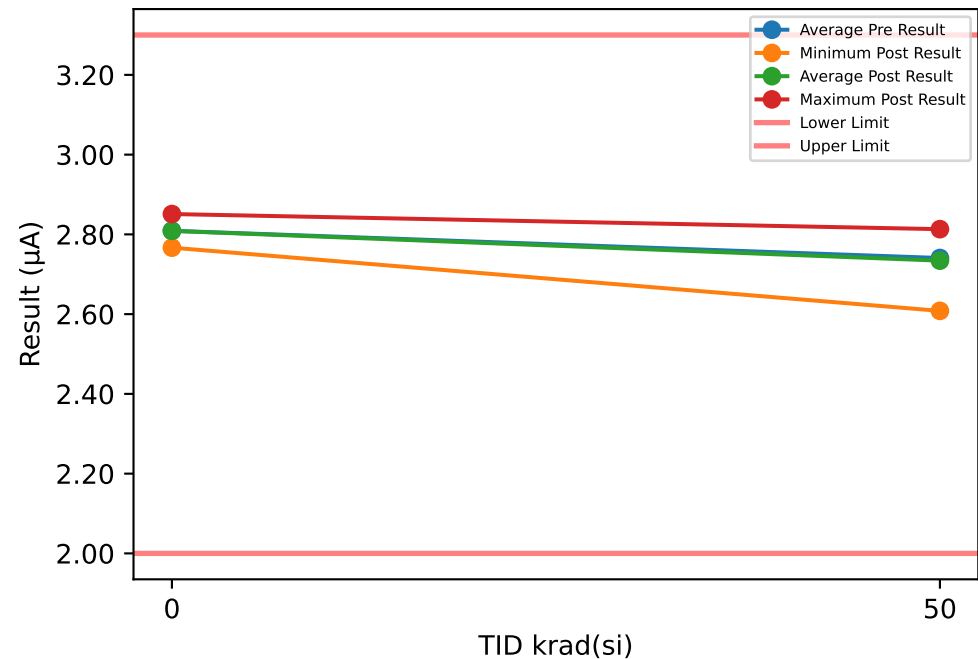


Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.7706	2.8131	2.8556	0.060104	2.7708	2.8133	2.8559	0.060175	0.0002	0.00025	0.0003	7.0711e-05
50	2.6601	2.7445	2.8001	0.047602	2.6109	2.7377	2.8177	0.062766	-0.0492	-0.00673	0.0216	0.023591

Device Test: 18.33 I_SS(CURRENT|SS_0p3V/SS/4.5/4.5/0/1000/4.5/1MHz//@I_SS)

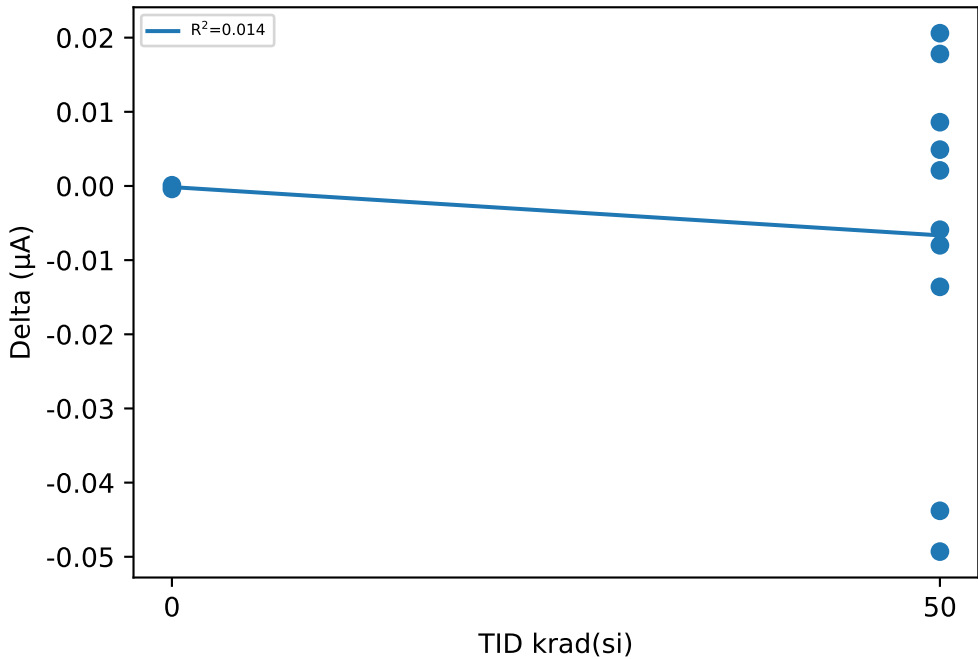
TID vs Result Stats



Test Results (Lower Limit = 2.0, Upper Limit = 3.3 (µA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	2.8509	2.851	0.0001
2	0	Correlation	2.7671	2.7667	-0.0004
4	50	Bias	2.7349	2.7527	0.0178
6	50	Bias	2.7252	2.6814	-0.0438
7	50	Bias	2.7956	2.7876	-0.008
8	50	Bias	2.7539	2.7625	0.0086
9	50	Bias	2.7582	2.7446	-0.0136
11	50	Unbias	2.7299	2.724	-0.0059
12	50	Unbias	2.6575	2.6082	-0.0493
13	50	Unbias	2.6737	2.6786	0.0049
14	50	Unbias	2.7863	2.7884	0.0021
15	50	Unbias	2.7925	2.8131	0.0206

TID vs Post - Pre Exposure Delta

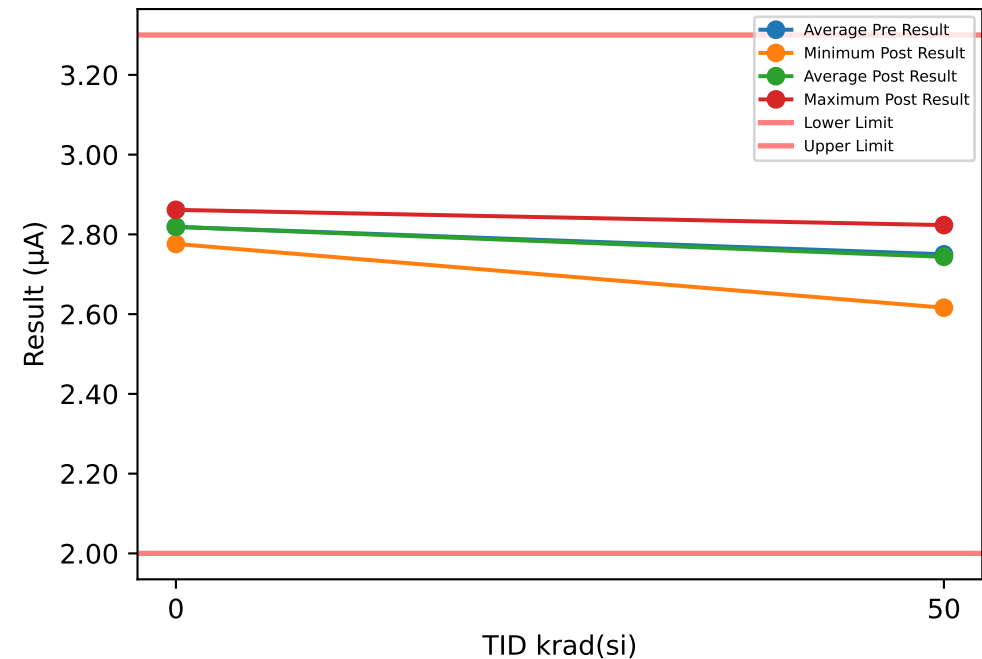


Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.7671	2.809	2.8509	0.059256	2.7667	2.8089	2.851	0.059609	-0.0004	-0.00015	0.0001	0.00035355
50	2.6575	2.7408	2.7956	0.04721	2.6082	2.7341	2.8131	0.062472	-0.0493	-0.00666	0.0206	0.023647

Device Test: 18.37 I_SS(CURRENT|SS_0p3V/SS/5/5/0/1000/5/1MHz//@I_SS)

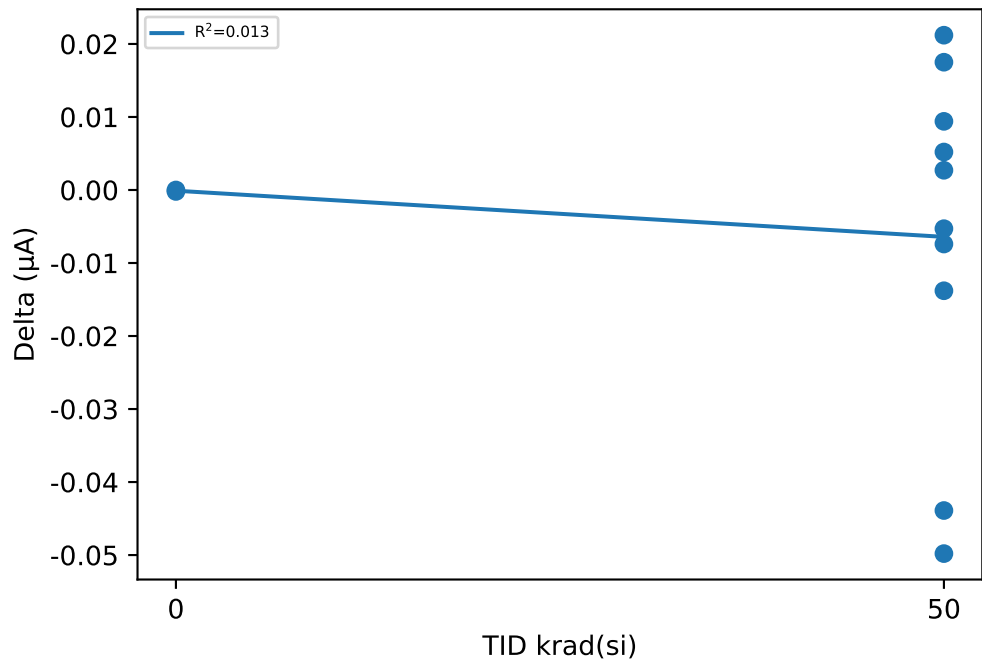
TID vs Result Stats



Test Results (Lower Limit = 2.0, Upper Limit = 3.3 (µA))

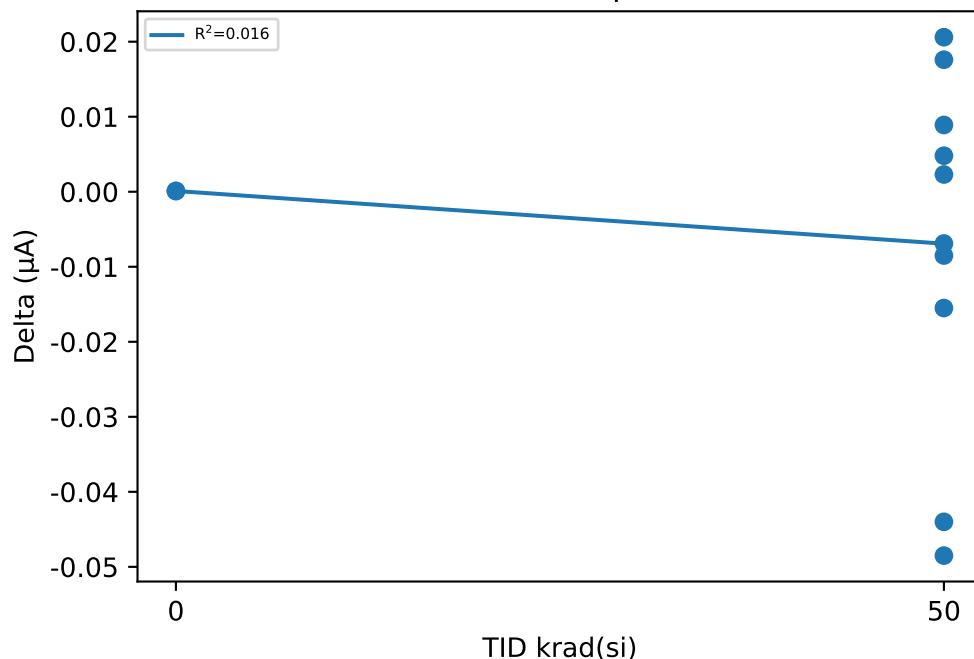
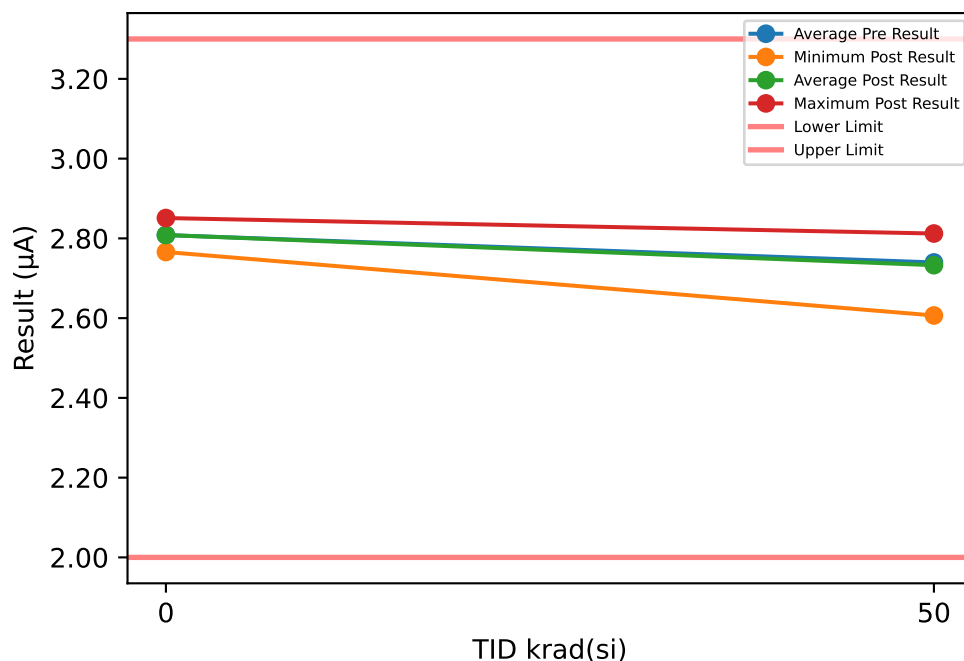
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	2.8615	2.8615	0
2	0	Correlation	2.7763	2.7761	-0.0002
4	50	Bias	2.7446	2.7621	0.0175
6	50	Bias	2.7348	2.6909	-0.0439
7	50	Bias	2.8052	2.7978	-0.0074
8	50	Bias	2.7635	2.7729	0.0094
9	50	Bias	2.7673	2.7535	-0.0138
11	50	Unbias	2.7392	2.7339	-0.0053
12	50	Unbias	2.6659	2.6161	-0.0498
13	50	Unbias	2.6823	2.6875	0.0052
14	50	Unbias	2.7958	2.7985	0.0027
15	50	Unbias	2.8021	2.8233	0.0212

TID vs Post - Pre Exposure Delta



Test Statistics (µA)

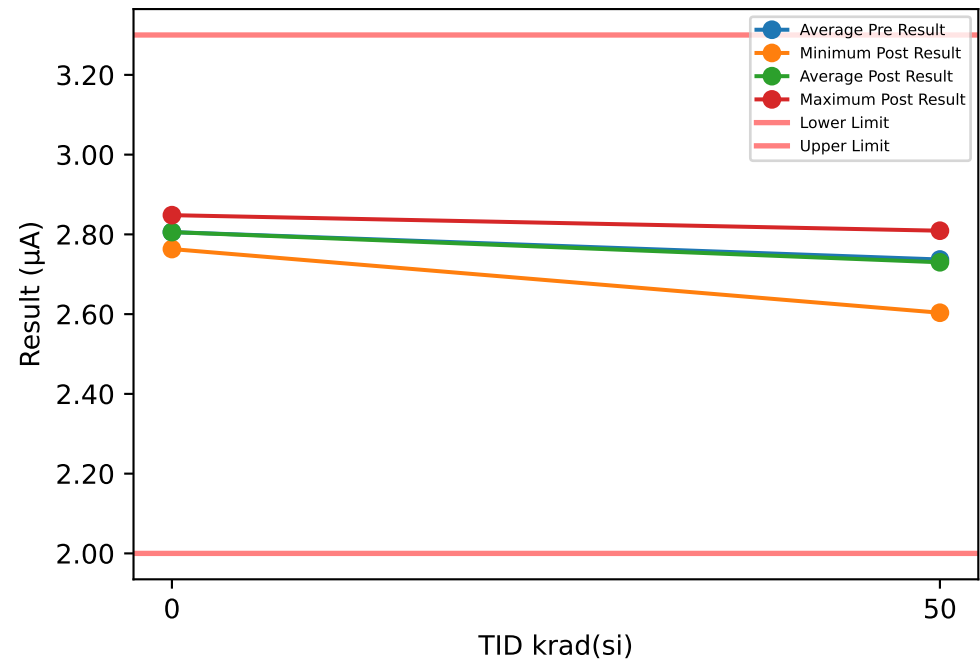
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.7763	2.8189	2.8615	0.060245	2.7761	2.8188	2.8615	0.060387	-0.0002	-0.0001	0	0.00014142
50	2.6659	2.7501	2.8052	0.047579	2.6161	2.7437	2.8233	0.063138	-0.0498	-0.00642	0.0212	0.023914



Test

Device Test: 18.45 I_SS(CURRENT|SS_0p3V/SS/14/14/0/1000/5/1MHz//@I_SS)

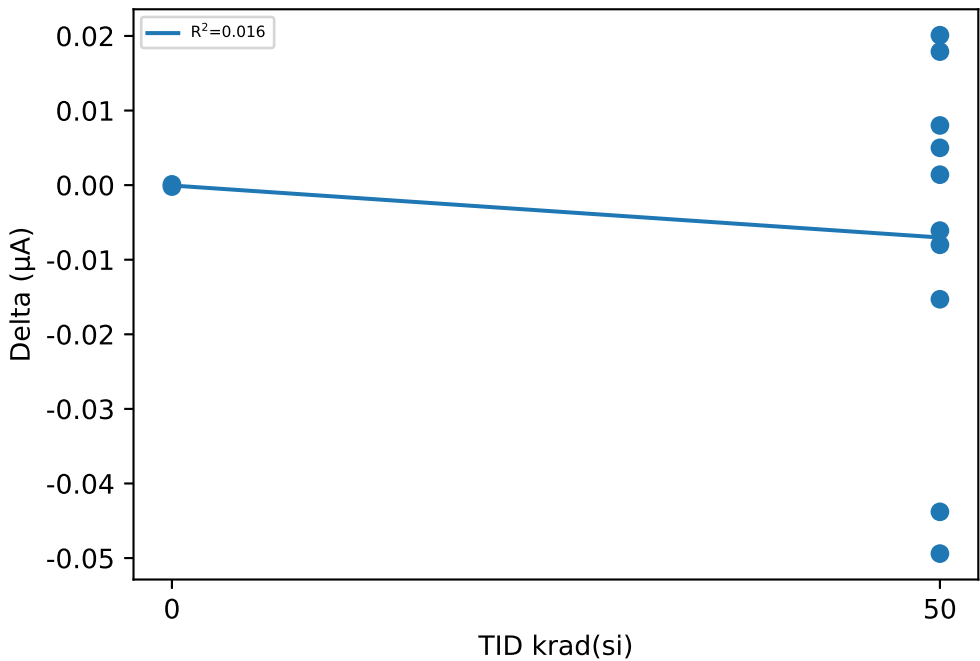
TID vs Result Stats



Test Results (Lower Limit = 2.0, Upper Limit = 3.3 (µA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	2.8481	2.8482	0.0001
2	0	Correlation	2.7634	2.7632	-0.0002
4	50	Bias	2.7312	2.7491	0.0179
6	50	Bias	2.7212	2.6774	-0.0438
7	50	Bias	2.7922	2.7842	-0.008
8	50	Bias	2.7505	2.7585	0.008
9	50	Bias	2.7548	2.7395	-0.0153
11	50	Unbias	2.7257	2.7196	-0.0061
12	50	Unbias	2.6529	2.6035	-0.0494
13	50	Unbias	2.67	2.675	0.005
14	50	Unbias	2.783	2.7844	0.0014
15	50	Unbias	2.7891	2.8092	0.0201

TID vs Post - Pre Exposure Delta

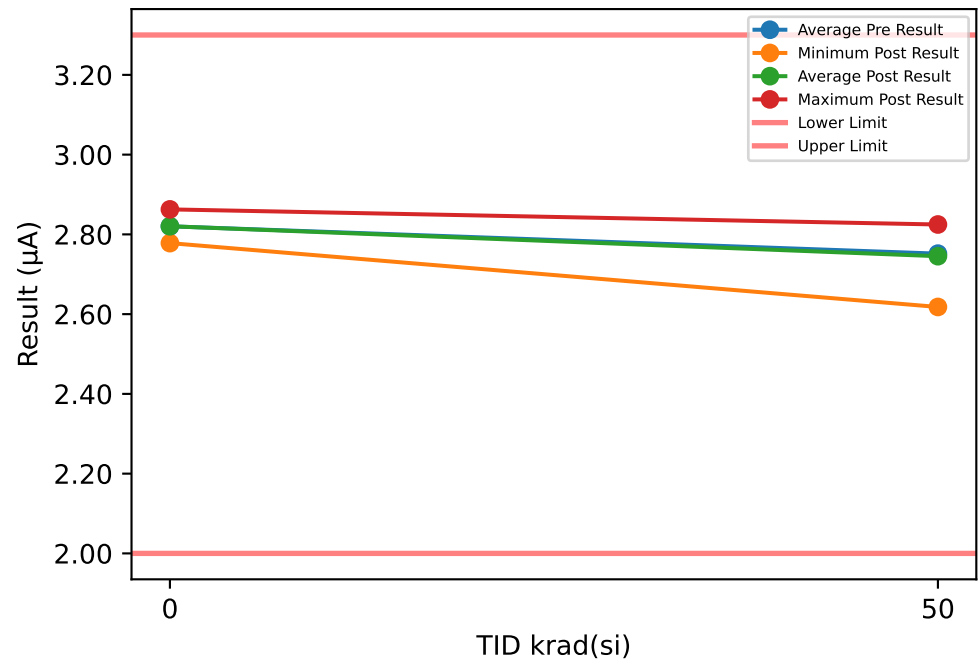


Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.7634	2.8058	2.8481	0.059892	2.7632	2.8057	2.8482	0.060104	-0.0002	-5e-05	0.0001	0.00021213
50	2.6529	2.7371	2.7922	0.04755	2.6035	2.73	2.8092	0.062662	-0.0494	-0.00702	0.0201	0.023609

Device Test: 18.5 I_SS(CURRENT|SS_0p3V/SS/5/5/0/1000/5/100kHz//@I_SS)

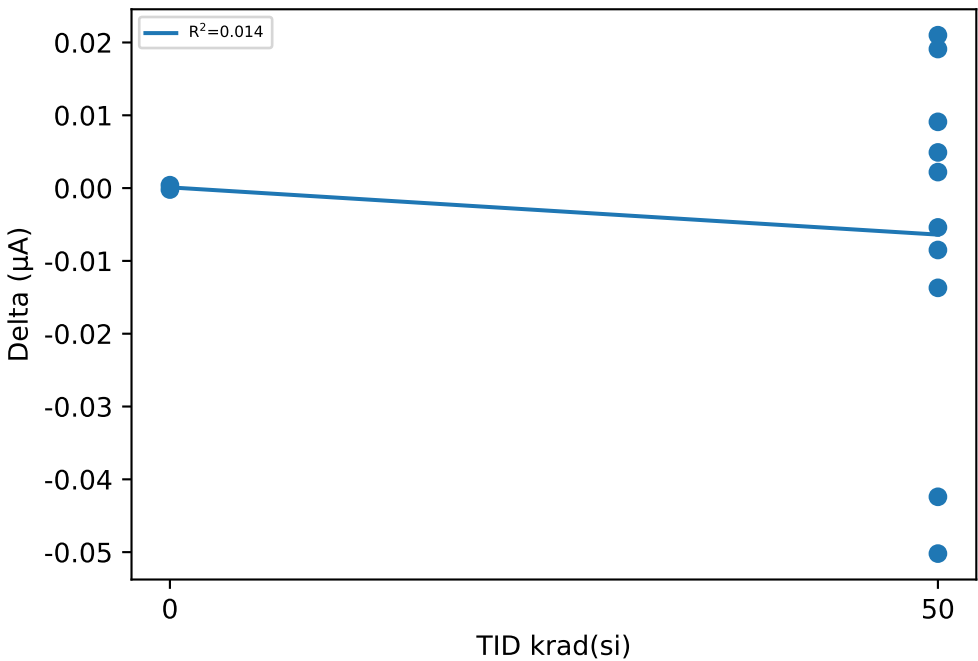
TID vs Result Stats



Test Results (Lower Limit = 2.0, Upper Limit = 3.3 (µA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	2.8629	2.8627	-0.0002
2	0	Correlation	2.7777	2.7781	0.0004
4	50	Bias	2.7457	2.7648	0.0191
6	50	Bias	2.7359	2.6935	-0.0424
7	50	Bias	2.8069	2.7984	-0.0085
8	50	Bias	2.765	2.7741	0.0091
9	50	Bias	2.769	2.7553	-0.0137
11	50	Unbias	2.7409	2.7355	-0.0054
12	50	Unbias	2.6682	2.618	-0.0502
13	50	Unbias	2.684	2.6889	0.0049
14	50	Unbias	2.7975	2.7997	0.0022
15	50	Unbias	2.8038	2.8248	0.021

TID vs Post - Pre Exposure Delta

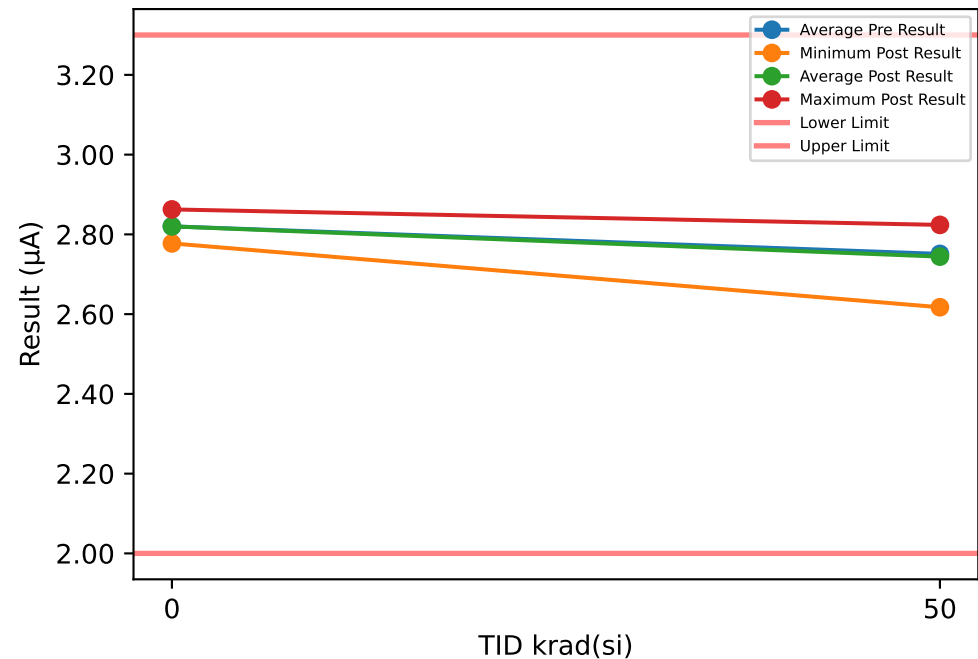


Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.7777	2.8203	2.8629	0.060245	2.7781	2.8204	2.8627	0.059821	-0.0002	0.0001	0.0004	0.00042426
50	2.6682	2.7517	2.8069	0.047485	2.618	2.7453	2.8248	0.062871	-0.0502	-0.00639	0.021	0.023842

Device Test: 18.9 I_SS(CURRENT|SS_0p3V/SS/12/12/0/1000/5/100kHz//@I_SS)

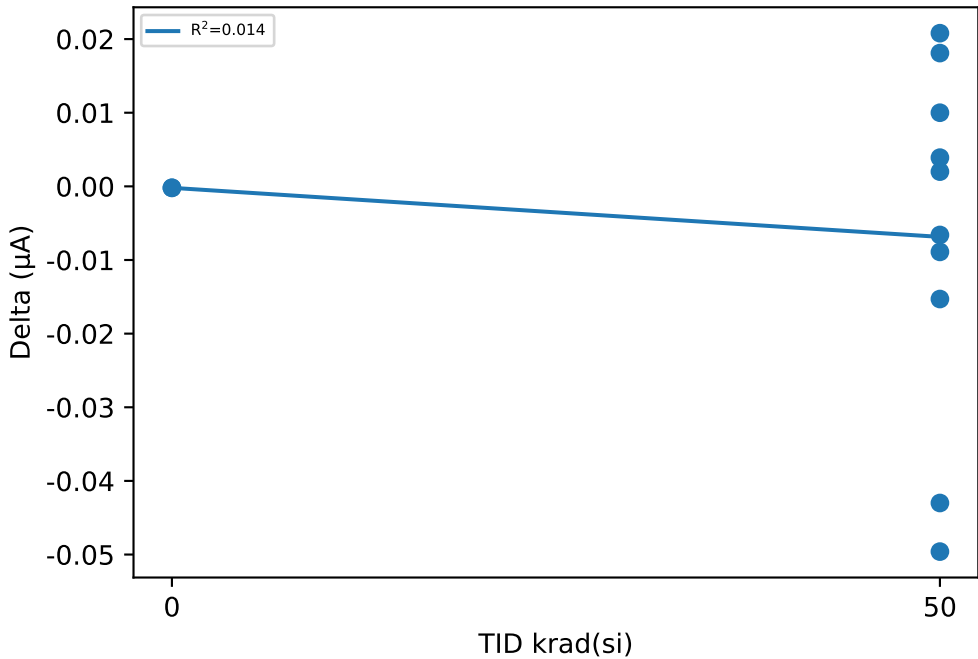
TID vs Result Stats



Test Results (Lower Limit = 2.0, Upper Limit = 3.3 (µA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	2.8628	2.8626	-0.0002
2	0	Correlation	2.7776	2.7774	-0.0002
4	50	Bias	2.7453	2.7634	0.0181
6	50	Bias	2.7358	2.6928	-0.043
7	50	Bias	2.8063	2.7974	-0.0089
8	50	Bias	2.7643	2.7743	0.01
9	50	Bias	2.7687	2.7534	-0.0153
11	50	Unbias	2.7399	2.7333	-0.0066
12	50	Unbias	2.6669	2.6173	-0.0496
13	50	Unbias	2.6837	2.6876	0.0039
14	50	Unbias	2.7967	2.7987	0.002
15	50	Unbias	2.803	2.8238	0.0208

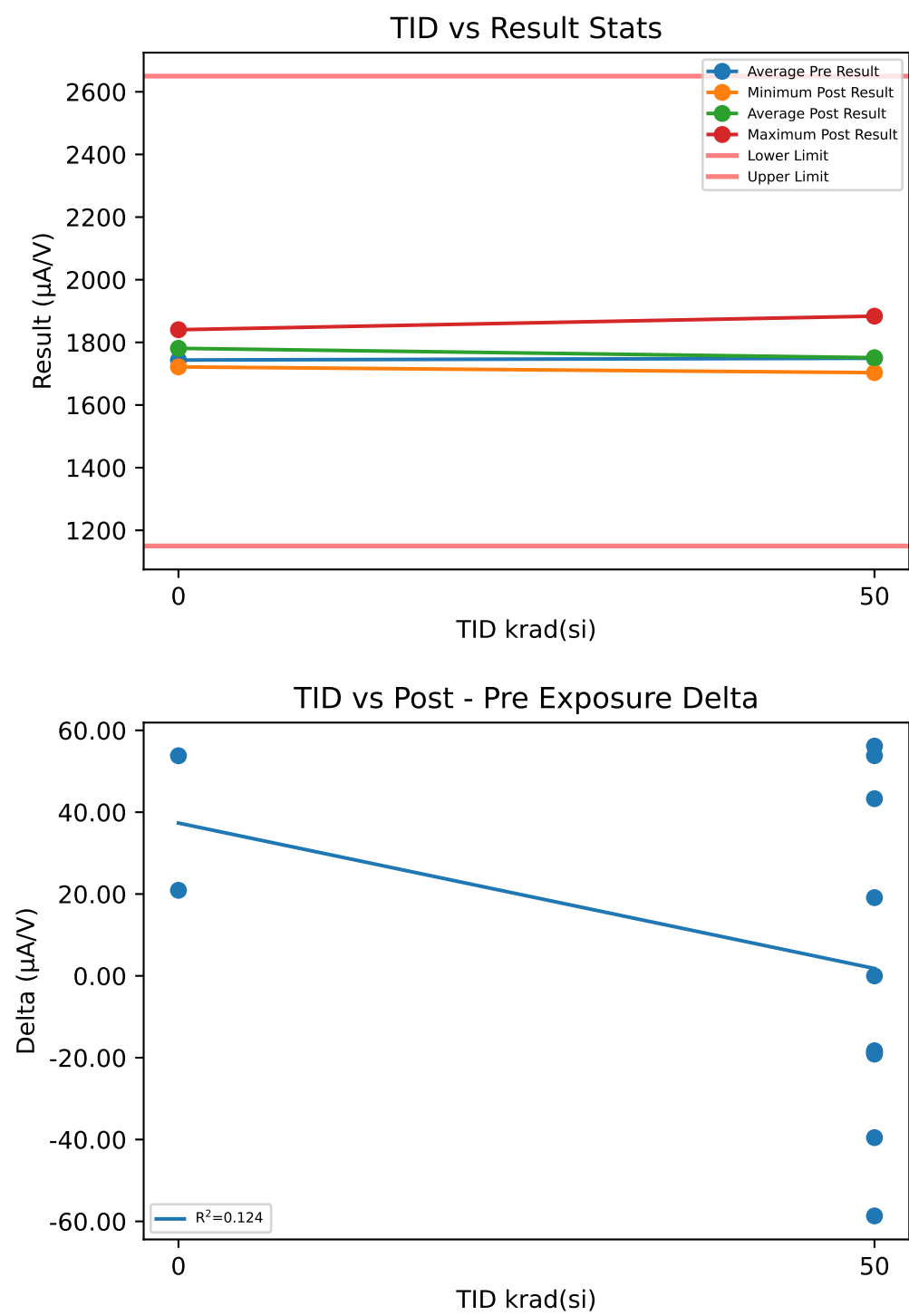
TID vs Post - Pre Exposure Delta



Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.7776	2.8202	2.8628	0.060245	2.7774	2.82	2.8626	0.060245	-0.0002	-0.0002	-0.0002	0
50	2.6669	2.7511	2.8063	0.047527	2.6173	2.7442	2.8238	0.062861	-0.0496	-0.00686	0.0208	0.023746

Device Test: 19.1 EA_GM(LEVEL|TRANSCONDUCTANCE//4.5/4.5/0/0/4.5/500kHz//@EA_GM)



Test Results (Lower Limit = 1150.0, Upper Limit = 2650.0 (µA/V))

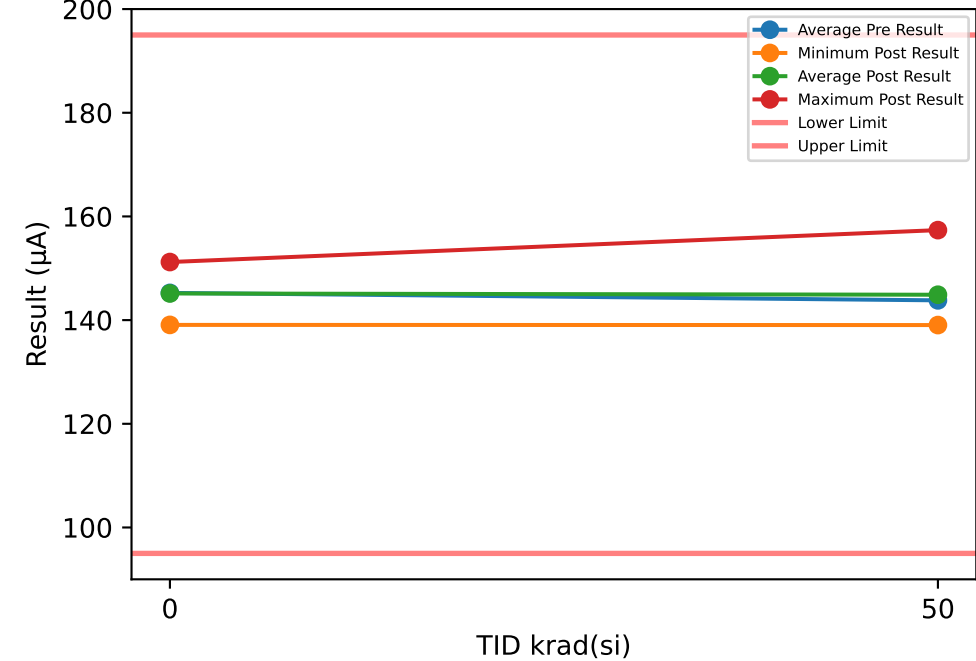
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1819.5	1840.4	20.906
2	0	Correlation	1667.8	1721.6	53.793
4	50	Bias	1740.4	1759.5	19.119
6	50	Bias	1799	1759.5	-39.536
7	50	Bias	1667.8	1721.6	53.81
8	50	Bias	1703.3	1759.5	56.154
9	50	Bias	1740.4	1721.6	-18.708
11	50	Unbias	1759.5	1740.4	-19.128
12	50	Unbias	1721.6	1703.3	-18.301
13	50	Unbias	1799	1740.4	-58.673
14	50	Unbias	1721.6	1721.6	-0.0089
15	50	Unbias	1840.4	1883.7	43.3

Test Statistics (µA/V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1667.8	1743.7	1819.5	107.2	1721.6	1781	1840.4	83.95	20.906	37.35	53.793	23.254
50	1667.8	1749.3	1840.4	51.407	1703.3	1751.1	1883.7	50.447	-58.673	1.8028	56.154	39.879

Device Test: 19.10 EA_I_SOURCE(CURRENT|EA_SOURCE//12/12/0/0/5/500kHz//@EA_I_SOURCE)

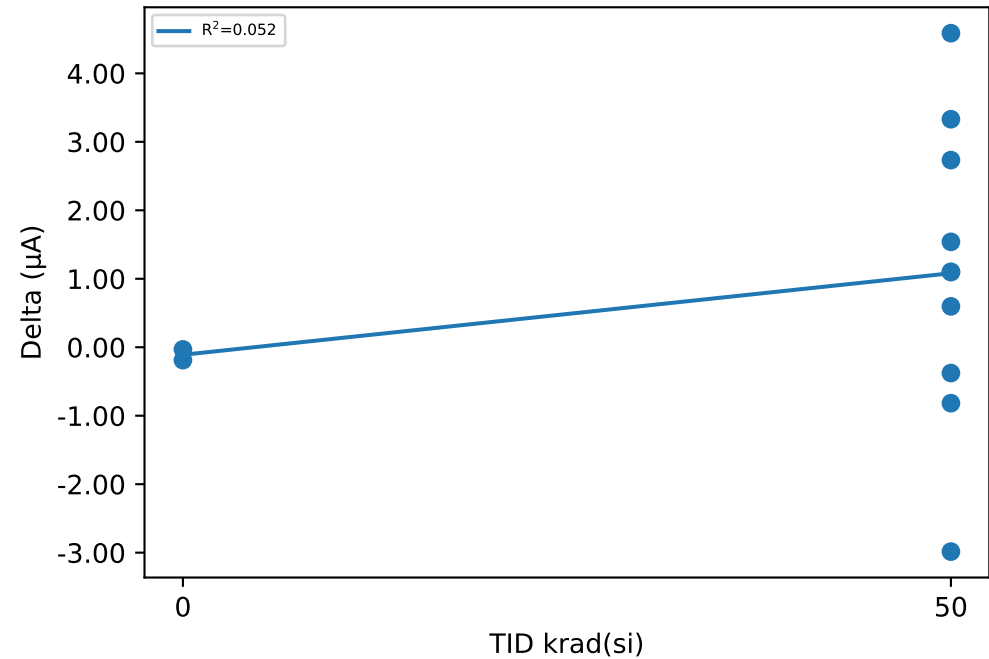
TID vs Result Stats



Test Results (Lower Limit = 95.0, Upper Limit = 195.0 (µA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	151.39	151.2	-0.1885
2	0	Correlation	139.11	139.08	-0.0314
4	50	Bias	141.62	142.72	1.0995
6	50	Bias	149.79	146.81	-2.9844
7	50	Bias	138.48	139.08	0.5969
8	50	Bias	143.07	145.8	2.7331
9	50	Bias	142.6	141.78	-0.8168
11	50	Unbias	144.26	145.8	1.5393
12	50	Unbias	142.66	142.28	-0.3769
13	50	Unbias	144.95	148.28	3.33
14	50	Unbias	137.95	139.05	1.0995
15	50	Unbias	152.77	157.36	4.5865

TID vs Post - Pre Exposure Delta

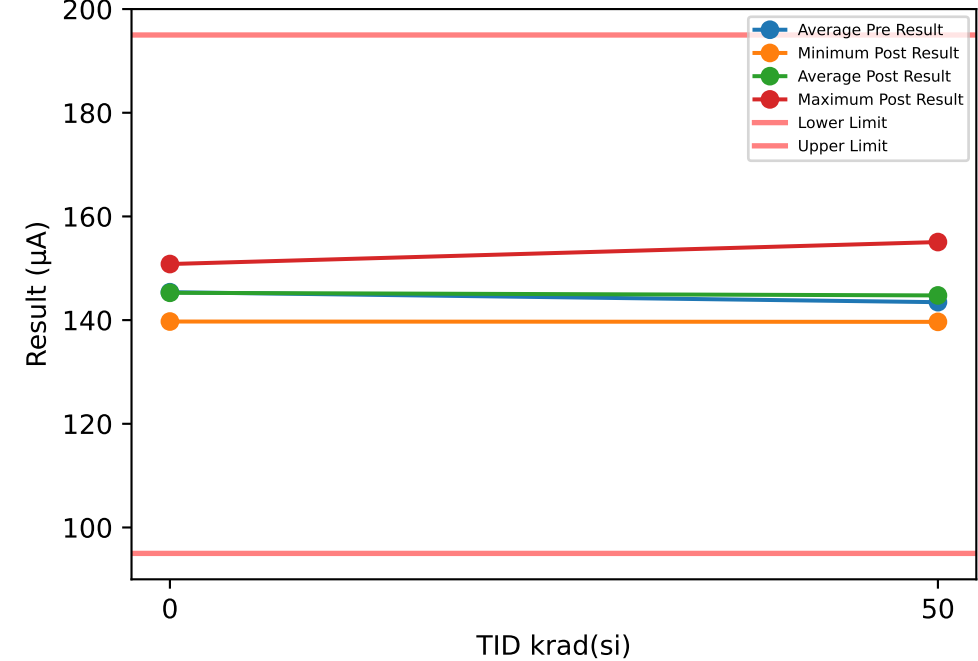


Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	139.11	145.25	151.39	8.6855	139.08	145.14	151.2	8.5744	-0.1885	-0.10995	-0.0314	0.11109
50	137.95	143.81	152.77	4.5771	139.05	144.9	157.36	5.39	-2.9844	1.0807	4.5865	2.1801

Device Test: 19.11 EA_I_SINK(CURRENT|EA_SINK//12/12/0/0/5/500kHz//@EA_I_SINK)

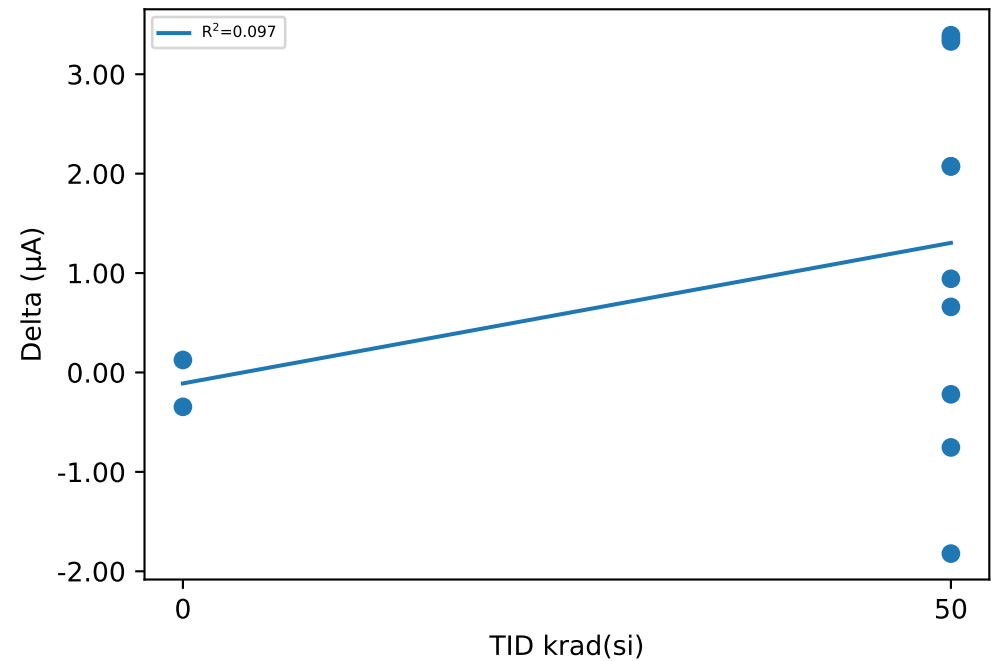
TID vs Result Stats



Test Results (Lower Limit = 95.0, Upper Limit = 195.0 (µA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	150.69	150.82	0.1256
2	0	Correlation	140.07	139.73	-0.3456
4	50	Bias	142.34	144.41	2.0734
6	50	Bias	149.75	147.93	-1.822
7	50	Bias	139.01	139.67	0.6597
8	50	Bias	143.4	146.8	3.3928
9	50	Bias	143.5	143.28	-0.2199
11	50	Unbias	142.37	143.31	0.9425
12	50	Unbias	141.36	140.61	-0.754
13	50	Unbias	143.25	146.58	3.3299
14	50	Unbias	137.94	140.01	2.0733
15	50	Unbias	151.7	155.06	3.3614

TID vs Post - Pre Exposure Delta

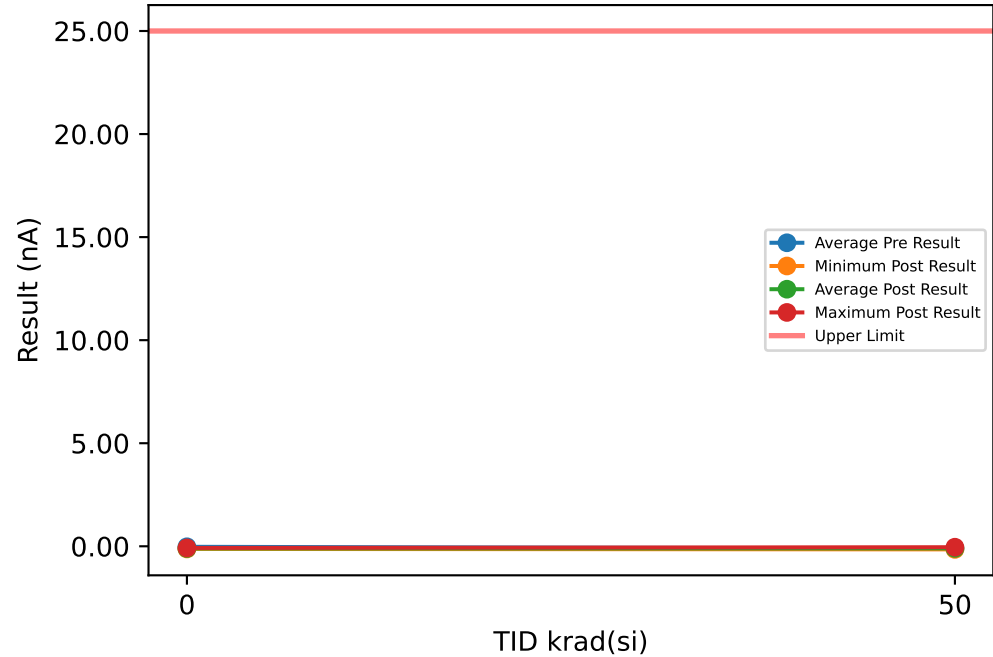


Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	140.07	145.38	150.69	7.5082	139.73	145.27	150.82	7.8414	-0.3456	-0.11	0.1256	0.33319
50	137.94	143.46	151.7	4.2773	139.67	144.76	155.06	4.6394	-1.822	1.3037	3.3928	1.8487

Device Test: 19.12 EA_IB(CURRENT|EA//12/12/0/0/5/500kHz//@EA_IB)

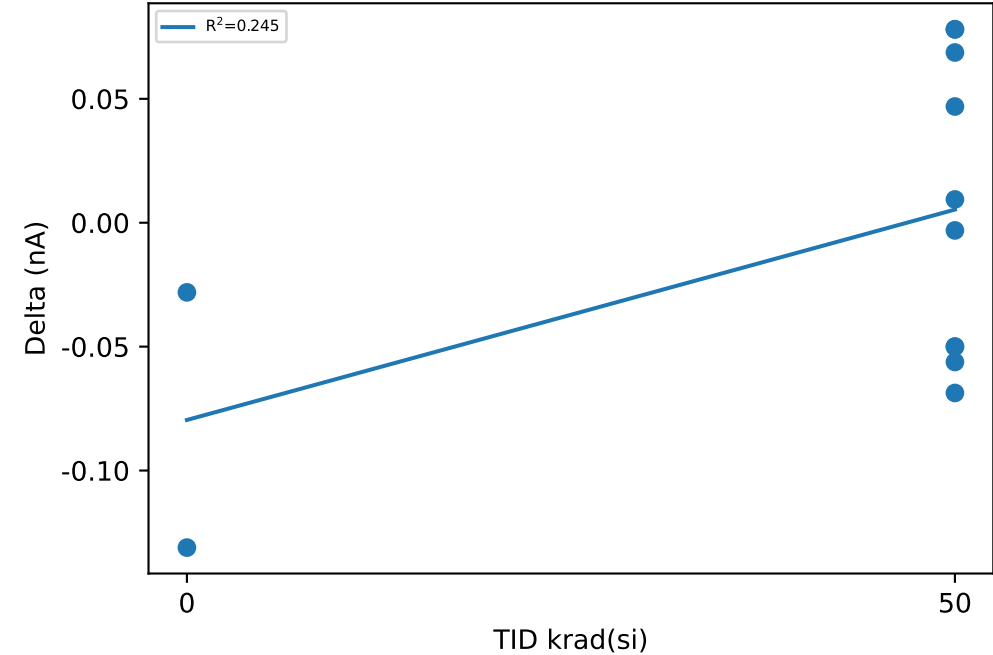
TID vs Result Stats



Test Results (Upper Limit = 25.0 (nA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	-0.0514	-0.0795	-0.0281
2	0	Correlation	0.0017	-0.1294	-0.1311
4	50	Bias	-0.0857	-0.0763	0.0094
6	50	Bias	-0.1794	-0.1107	0.0687
7	50	Bias	-0.1481	-0.0701	0.078
8	50	Bias	-0.1232	-0.1263	-0.0031
9	50	Bias	-0.0482	-0.1169	-0.0687
11	50	Unbias	-0.1388	-0.0919	0.0469
12	50	Unbias	-0.1013	-0.1513	-0.05
13	50	Unbias	-0.0919	-0.1481	-0.0562
14	50	Unbias	-0.1232	-0.0451	0.0781
15	50	Unbias	-0.0326	-0.0826	-0.05

TID vs Post - Pre Exposure Delta

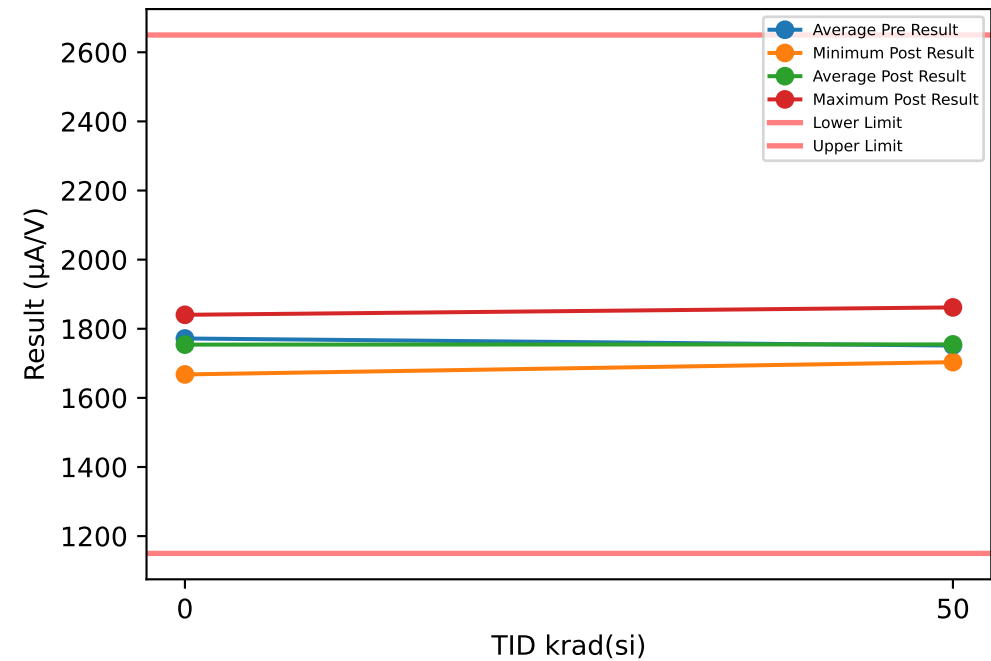


Test Statistics (nA)

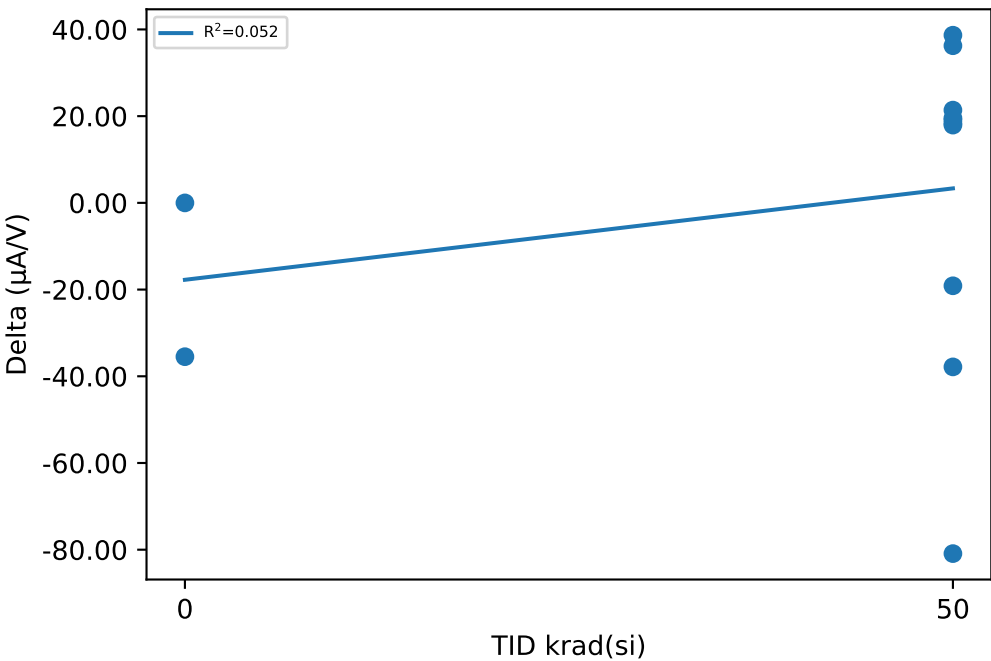
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.0514	-0.02485	0.0017	0.037547	-0.1294	-0.10445	-0.0795	0.035285	-0.1311	-0.0796	-0.0281	0.072832
50	-0.1794	-0.10724	-0.0326	0.044936	-0.1513	-0.10193	-0.0451	0.034702	-0.0687	0.00531	0.0781	0.059439

Device Test: 19.13 EA_GM(LEVEL|TRANSCONDUCTANCE//14/14/0/0/5/500kHz//@EA_GM)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1150.0, Upper Limit = 2650.0 (µA/V))

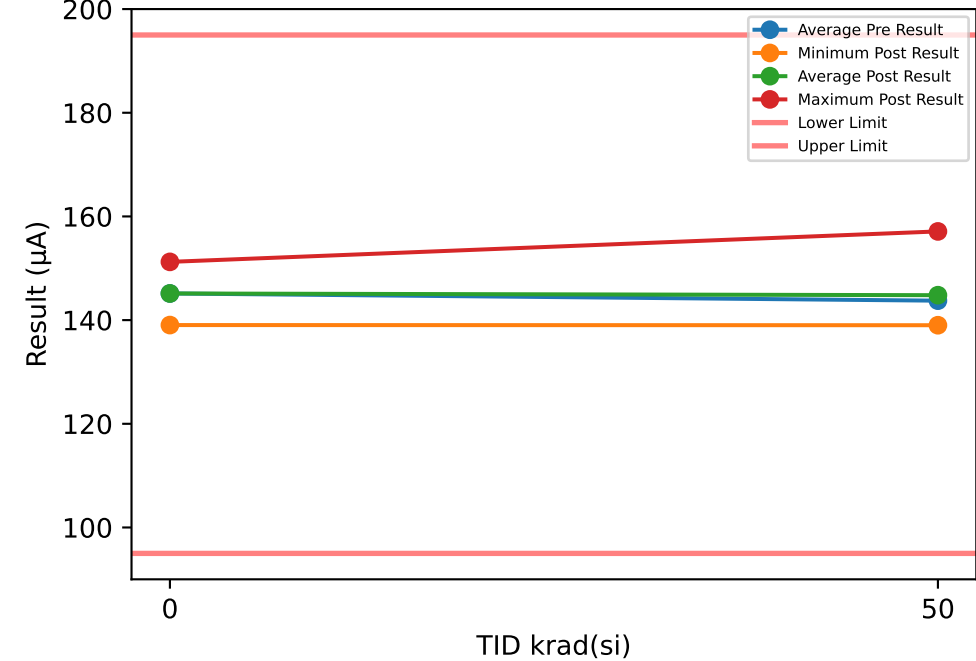
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1840.4	1840.4	-0.0101
2	0	Correlation	1703.3	1667.8	-35.483
4	50	Bias	1759.5	1779	19.553
6	50	Bias	1840.4	1759.5	-80.899
7	50	Bias	1685.4	1703.3	17.933
8	50	Bias	1740.4	1759.5	19.119
9	50	Bias	1703.3	1721.6	18.327
11	50	Unbias	1740.4	1779	38.671
12	50	Unbias	1759.5	1721.6	-37.835
13	50	Unbias	1759.5	1740.4	-19.128
14	50	Unbias	1685.4	1721.6	36.242
15	50	Unbias	1840.4	1861.8	21.393

Test Statistics (µA/V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1703.3	1771.9	1840.4	96.917	1667.8	1754.1	1840.4	122	-35.483	-17.746	-0.0101	25.083
50	1685.4	1751.4	1840.4	55.074	1703.3	1754.7	1861.8	45.724	-80.899	3.3375	38.671	37.863

Device Test: 19.14 EA_I_SOURCE(CURRENT|EA_SOURCE//14/14/0/0/5/500kHz//@EA_I_SOURCE)

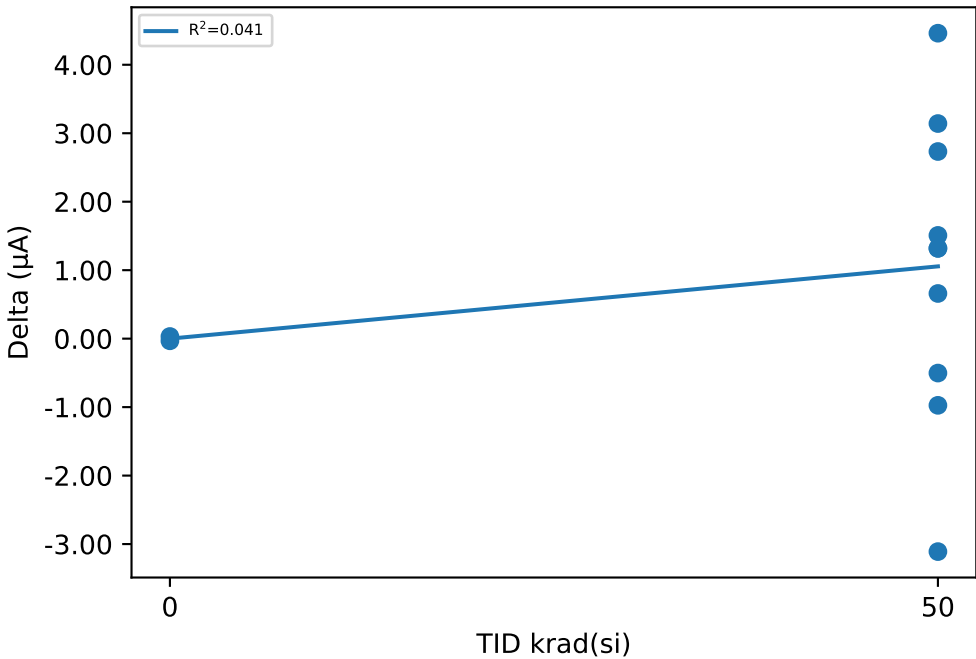
TID vs Result Stats



Test Results (Lower Limit = 95.0, Upper Limit = 195.0 (µA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	151.27	151.23	-0.0314
2	0	Correlation	139.01	139.05	0.0314
4	50	Bias	141.37	142.69	1.3194
6	50	Bias	149.7	146.59	-3.11
7	50	Bias	138.35	139.01	0.6597
8	50	Bias	142.97	145.71	2.7331
9	50	Bias	142.72	141.75	-0.9738
11	50	Unbias	144.23	145.74	1.5079
12	50	Unbias	142.66	142.16	-0.5026
13	50	Unbias	145.01	148.16	3.1415
14	50	Unbias	137.85	139.17	1.3194
15	50	Unbias	152.65	157.11	4.4609

TID vs Post - Pre Exposure Delta

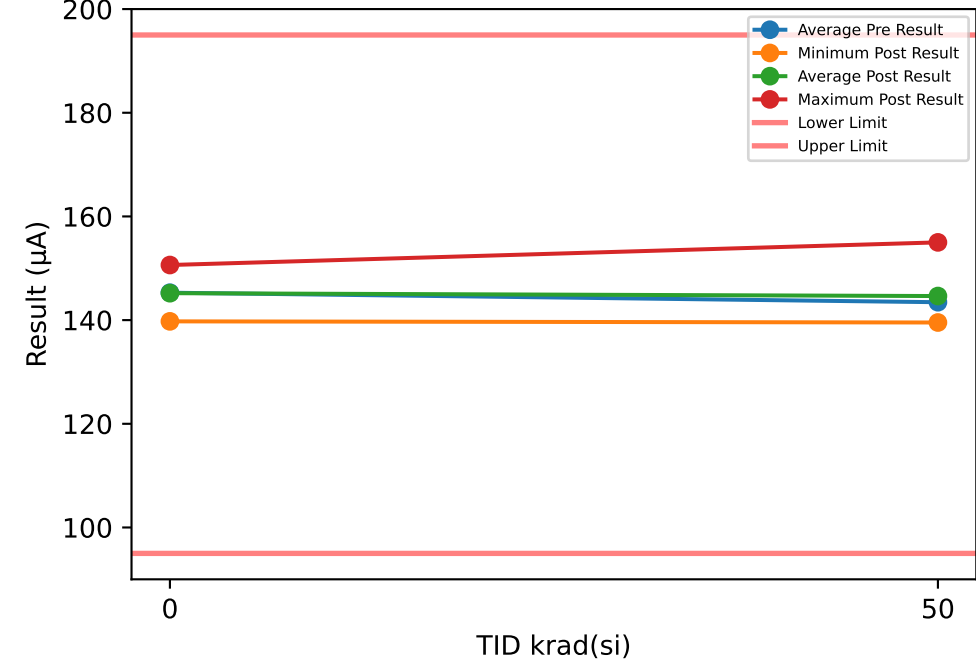


Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	139.01	145.14	151.27	8.6633	139.05	145.14	151.23	8.6189	-0.0314	0	0.0314	0.044406
50	137.85	143.75	152.65	4.5798	139.01	144.81	157.11	5.3081	-3.11	1.0556	4.4609	2.1899

Device Test: 19.15 EA_I_SINK(CURRENT|EA_SINK//14/14/0/0/5/500kHz//@EA_I_SINK)

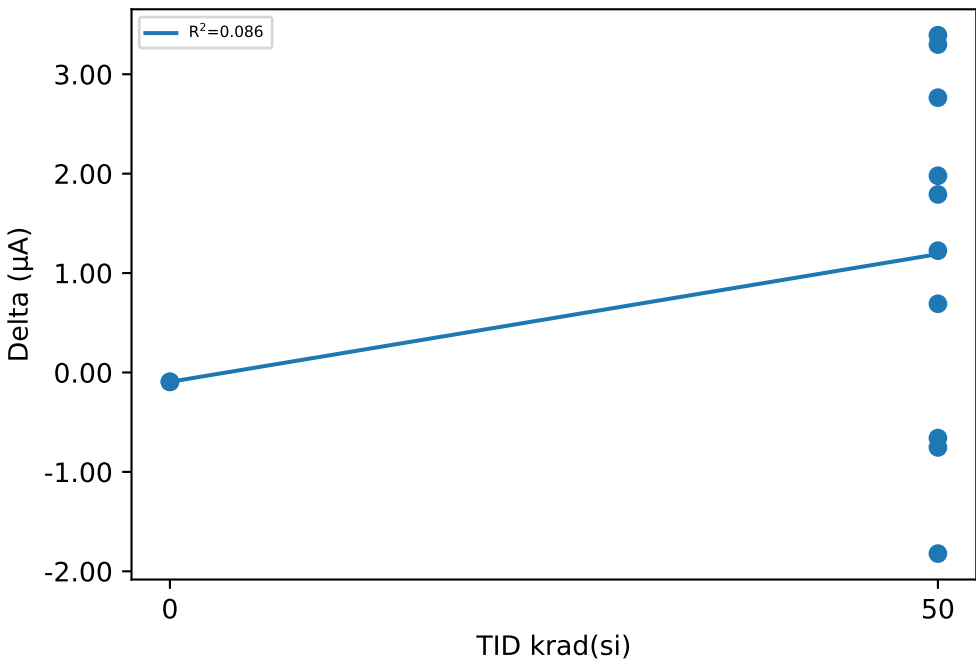
TID vs Result Stats



Test Results (Lower Limit = 95.0, Upper Limit = 195.0 (µA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	150.72	150.63	-0.0943
2	0	Correlation	139.85	139.76	-0.0943
4	50	Bias	142.37	144.16	1.7907
6	50	Bias	149.59	147.77	-1.822
7	50	Bias	138.85	139.54	0.6911
8	50	Bias	143.62	146.39	2.7645
9	50	Bias	143.56	142.81	-0.7539
11	50	Unbias	142.27	143.5	1.2252
12	50	Unbias	141.27	140.61	-0.6597
13	50	Unbias	143.18	146.58	3.3928
14	50	Unbias	138.13	140.11	1.9791
15	50	Unbias	151.7	155	3.2986

TID vs Post - Pre Exposure Delta

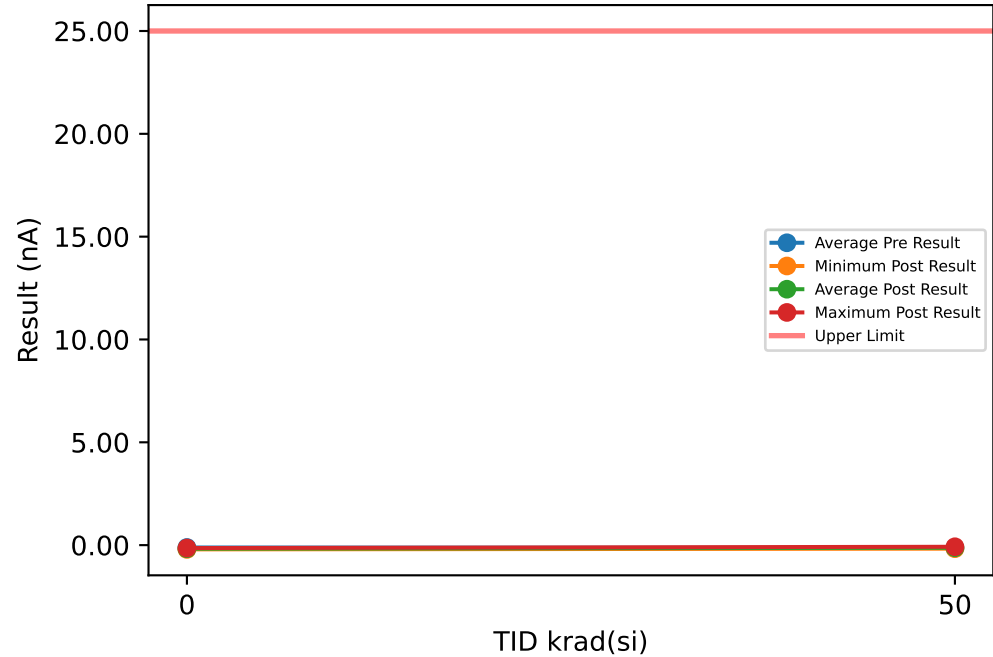


Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	139.85	145.29	150.72	7.6859	139.76	145.19	150.63	7.6859	-0.0943	-0.0943	-0.0943	2.0097e-14
50	138.13	143.45	151.7	4.2518	139.54	144.64	155	4.6138	-1.822	1.1906	3.3928	1.8038

Device Test: 19.16 EA_IB(CURRENT|EA//14/14/0/0/5/500kHz//@EA_IB)

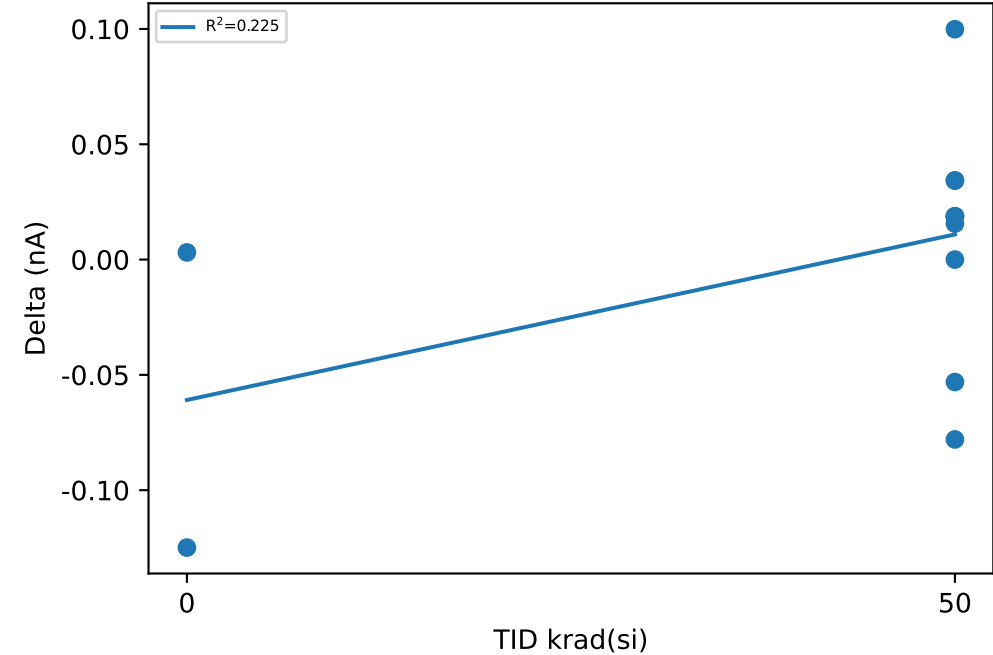
TID vs Result Stats



Test Results (Upper Limit = 25.0 (nA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	-0.145	-0.1419	0.0031
2	0	Correlation	-0.0826	-0.2075	-0.1249
4	50	Bias	-0.1731	-0.1388	0.0343
6	50	Bias	-0.1513	-0.1325	0.0188
7	50	Bias	-0.2293	-0.1294	0.0999
8	50	Bias	-0.1138	-0.0795	0.0343
9	50	Bias	-0.1169	-0.1169	0
11	50	Unbias	-0.0732	-0.1263	-0.0531
12	50	Unbias	-0.0951	-0.1731	-0.078
13	50	Unbias	-0.1544	-0.1357	0.0187
14	50	Unbias	-0.1263	-0.1076	0.0187
15	50	Unbias	-0.1544	-0.1388	0.0156

TID vs Post - Pre Exposure Delta

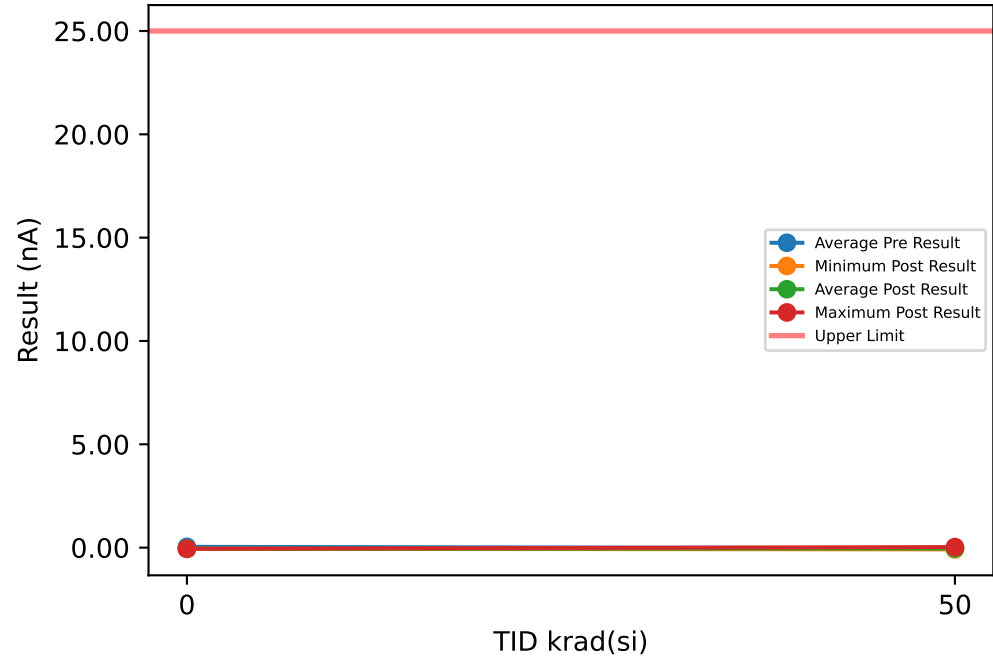


Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.145	-0.1138	-0.0826	0.044123	-0.2075	-0.1747	-0.1419	0.046386	-0.1249	-0.0609	0.0031	0.09051
50	-0.2293	-0.13878	-0.0732	0.044075	-0.1731	-0.12786	-0.0795	0.024136	-0.078	0.01092	0.0999	0.048694

Device Test: 19.17 EA_IB(CURRENT|EA//4.5/4.5/0/0/4.5/100kHz//@EA_IB)

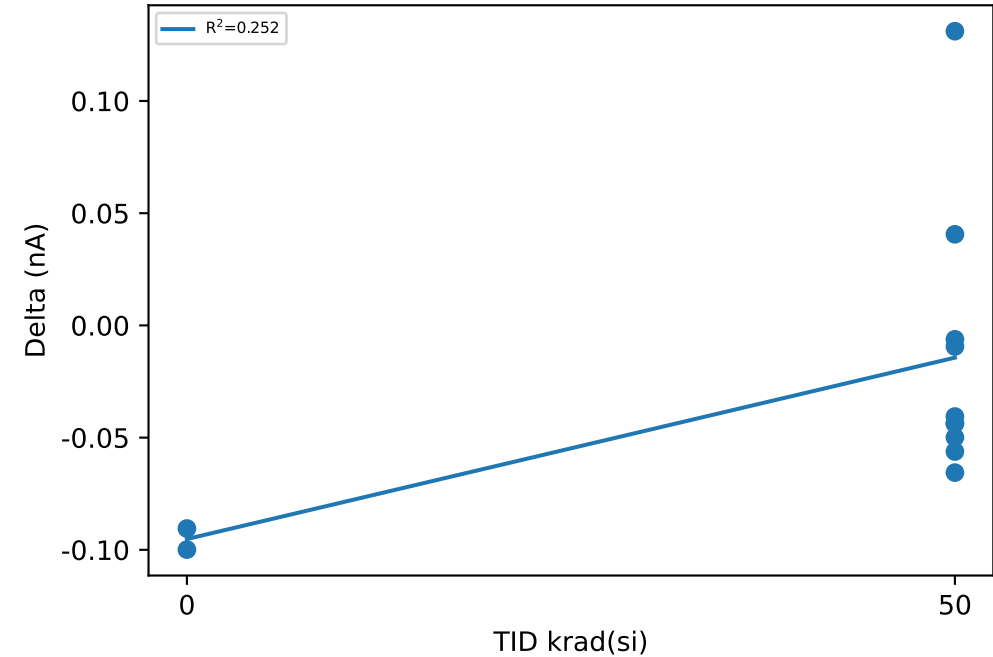
TID vs Result Stats



Test Results (Upper Limit = 25.0 (nA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.0329	-0.0576	-0.0905
2	0	Correlation	0.0454	-0.0545	-0.0999
4	50	Bias	-0.017	-0.0264	-0.0094
6	50	Bias	-0.0264	-0.0763	-0.0499
7	50	Bias	0.0423	-0.0233	-0.0656
8	50	Bias	-0.1044	0.0267	0.1311
9	50	Bias	-0.0639	-0.0701	-0.0062
11	50	Unbias	0.0204	-0.0358	-0.0562
12	50	Unbias	-0.0077	-0.0514	-0.0437
13	50	Unbias	-0.042	-0.0857	-0.0437
14	50	Unbias	-0.042	-0.0826	-0.0406
15	50	Unbias	-0.0358	0.0048	0.0406

TID vs Post - Pre Exposure Delta

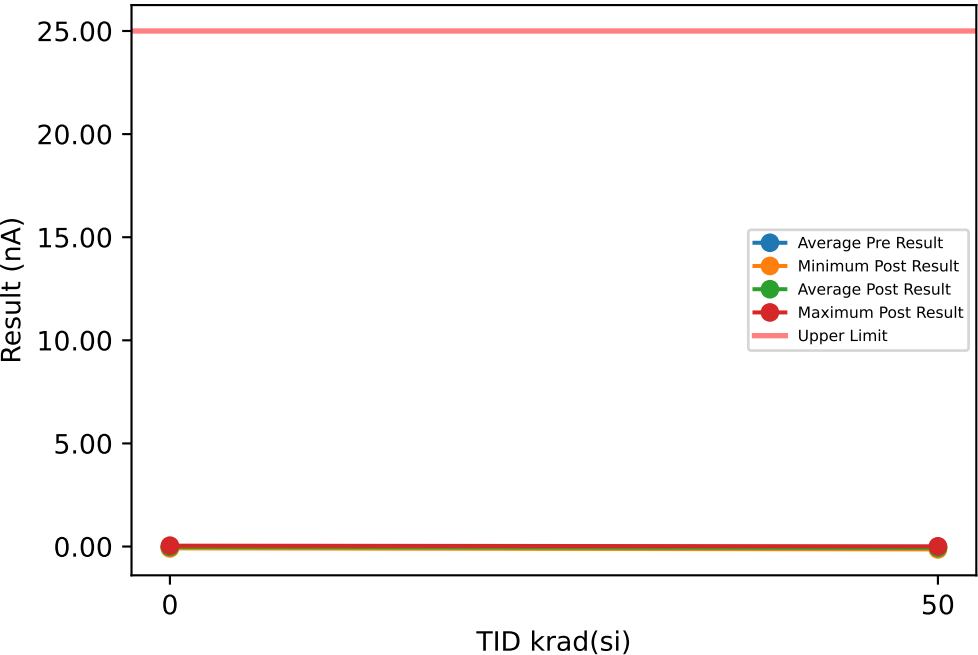


Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0329	0.03915	0.0454	0.0088388	-0.0576	-0.05605	-0.0545	0.002192	-0.0999	-0.0952	-0.0905	0.0066468
50	-0.1044	-0.02765	0.0423	0.041362	-0.0857	-0.04201	0.0267	0.03823	-0.0656	-0.01436	0.1311	0.059926

Device Test: 19.18 EA_IB(CURRENT|EA//4.5/4.5/0/0/4.5/1MHz//@EA_IB)

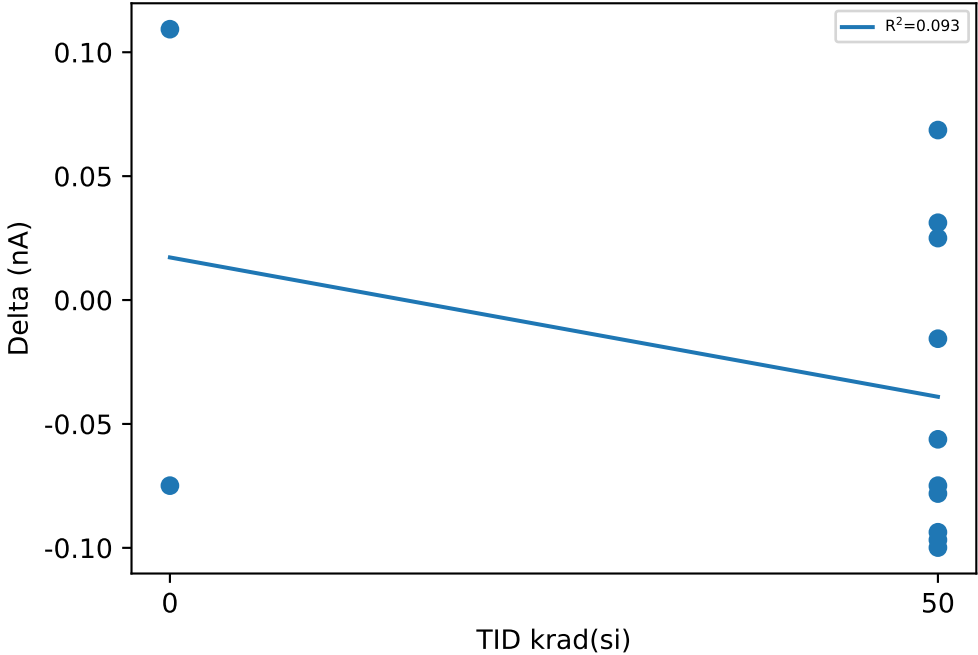
TID vs Result Stats



Test Results (Upper Limit = 25.0 (nA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	-0.067	0.0423	0.1093
2	0	Correlation	-0.0139	-0.0888	-0.0749
4	50	Bias	0.008	-0.0701	-0.0781
6	50	Bias	-0.0139	0.0111	0.025
7	50	Bias	-0.0919	-0.0607	0.0312
8	50	Bias	-0.042	-0.1388	-0.0968
9	50	Bias	-0.0108	-0.067	-0.0562
11	50	Unbias	-0.0919	-0.0233	0.0686
12	50	Unbias	0.0361	-0.0576	-0.0937
13	50	Unbias	0.0173	-0.0826	-0.0999
14	50	Unbias	-0.0295	-0.1044	-0.0749
15	50	Unbias	-0.0233	-0.0389	-0.0156

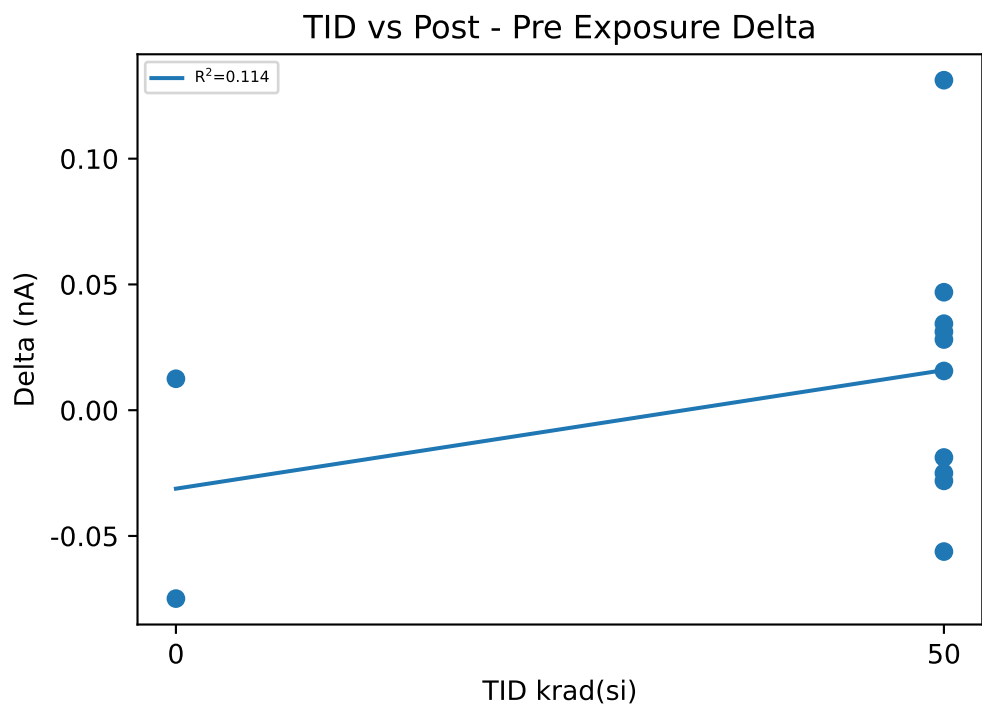
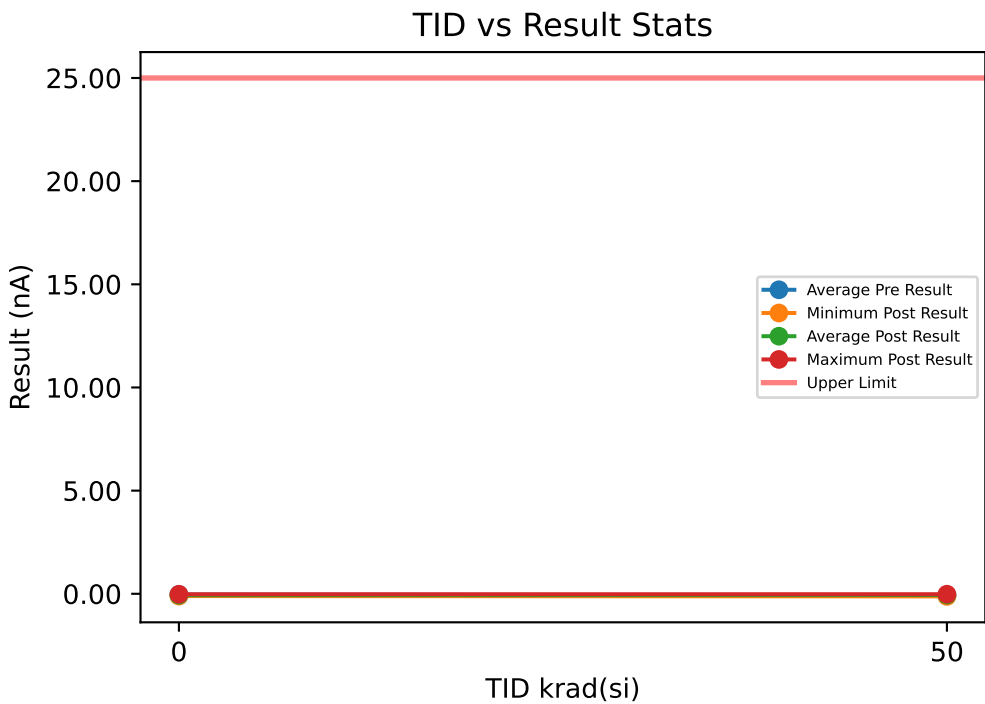
TID vs Post - Pre Exposure Delta



Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.067	-0.04045	-0.0139	0.037547	-0.0888	-0.02325	0.0423	0.092702	-0.0749	0.0172	0.1093	0.13025
50	-0.0919	-0.02419	0.0361	0.042417	-0.1388	-0.06323	0.0111	0.041622	-0.0999	-0.03904	0.0686	0.061738

Device Test: 19.19 EA_IB(CURRENT|EA//5/5/0/0/5/100kHz//@EA_IB)



Test Results (Upper Limit = 25.0 (nA))

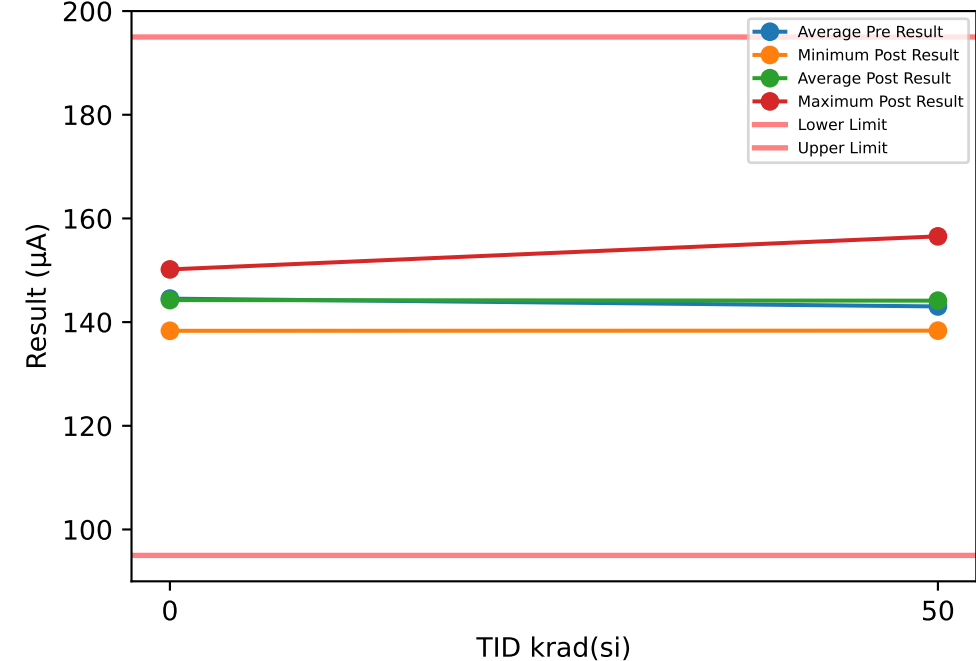
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	-0.0358	-0.1107	-0.0749
2	0	Correlation	-0.0358	-0.0233	0.0125
4	50	Bias	-0.0326	-0.0514	-0.0188
6	50	Bias	-0.0795	-0.0326	0.0469
7	50	Bias	-0.0951	-0.067	0.0281
8	50	Bias	-0.0857	-0.1107	-0.025
9	50	Bias	-0.1513	-0.0201	0.1312
11	50	Unbias	-0.0701	-0.1263	-0.0562
12	50	Unbias	-0.0795	-0.0451	0.0344
13	50	Unbias	-0.1013	-0.0701	0.0312
14	50	Unbias	-0.017	-0.0451	-0.0281
15	50	Unbias	-0.0545	-0.0389	0.0156

Test Statistics (nA)

krad(Si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.0358	-0.0358	-0.0358	0	-0.1107	-0.067	-0.0233	0.061801	-0.0749	-0.0312	0.0125	0.061801
50	-0.1513	-0.07666	-0.017	0.037492	-0.1263	-0.06073	-0.0201	0.034023	-0.0562	0.01593	0.1312	0.052696

Device Test: 19.2 EA_I_SOURCE(CURRENT|EA_SOURCE//4.5/4.5/0/0/4.5/500kHz//@EA_I_SOURCE)

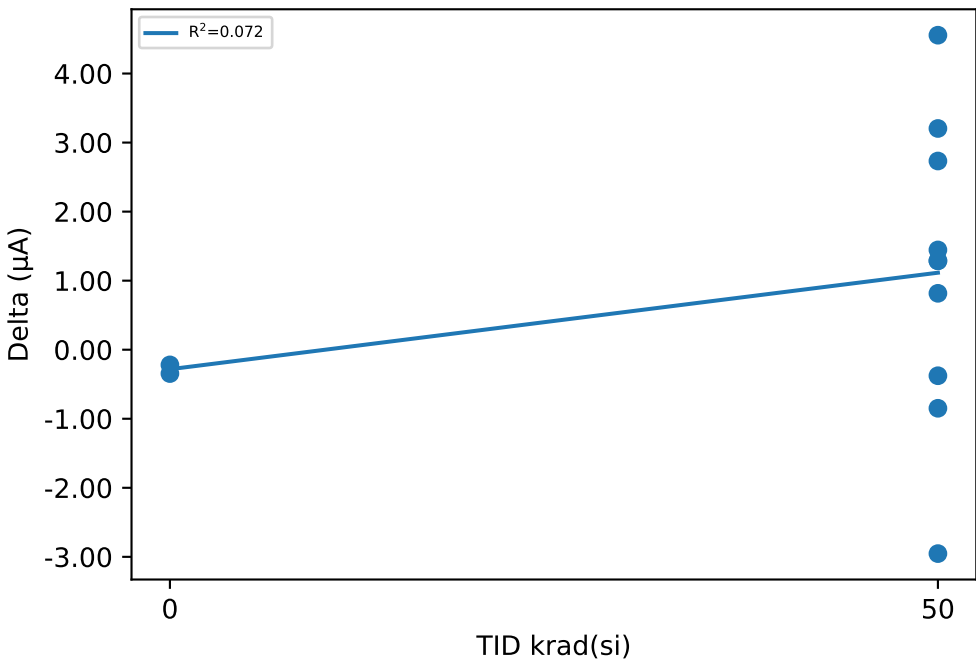
TID vs Result Stats



Test Results (Lower Limit = 95.0, Upper Limit = 195.0 (µA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	150.51	150.17	-0.3455
2	0	Correlation	138.54	138.32	-0.2199
4	50	Bias	140.65	141.94	1.288
6	50	Bias	149	146.05	-2.953
7	50	Bias	137.54	138.35	0.8168
8	50	Bias	142.19	144.92	2.7331
9	50	Bias	141.94	141.09	-0.8482
11	50	Unbias	143.57	145.01	1.445
12	50	Unbias	142	141.62	-0.377
13	50	Unbias	144.26	147.47	3.2043
14	50	Unbias	137.1	138.39	1.288
15	50	Unbias	151.99	156.54	4.5552

TID vs Post - Pre Exposure Delta

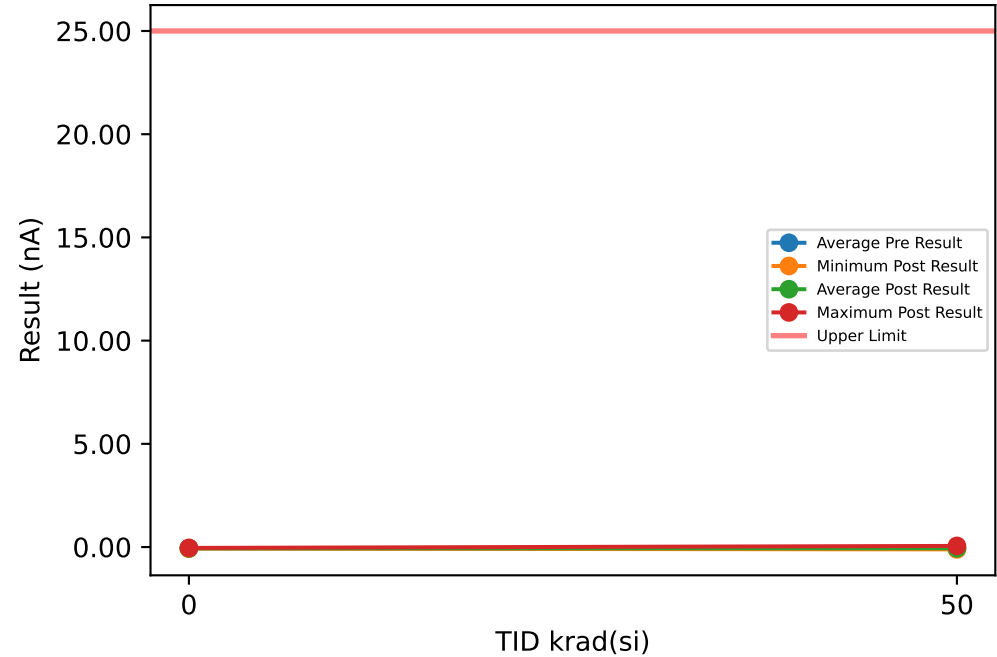


Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	138.54	144.53	150.51	8.4634	138.32	144.25	150.17	8.3745	-0.3455	-0.2827	-0.2199	0.088813
50	137.1	143.02	151.99	4.6158	138.35	144.14	156.54	5.3441	-2.953	1.1152	4.5552	2.1526

Device Test: 19.20 EA_IB(CURRENT|EA//5/5/0/0/5/1MHz//@EA_IB)

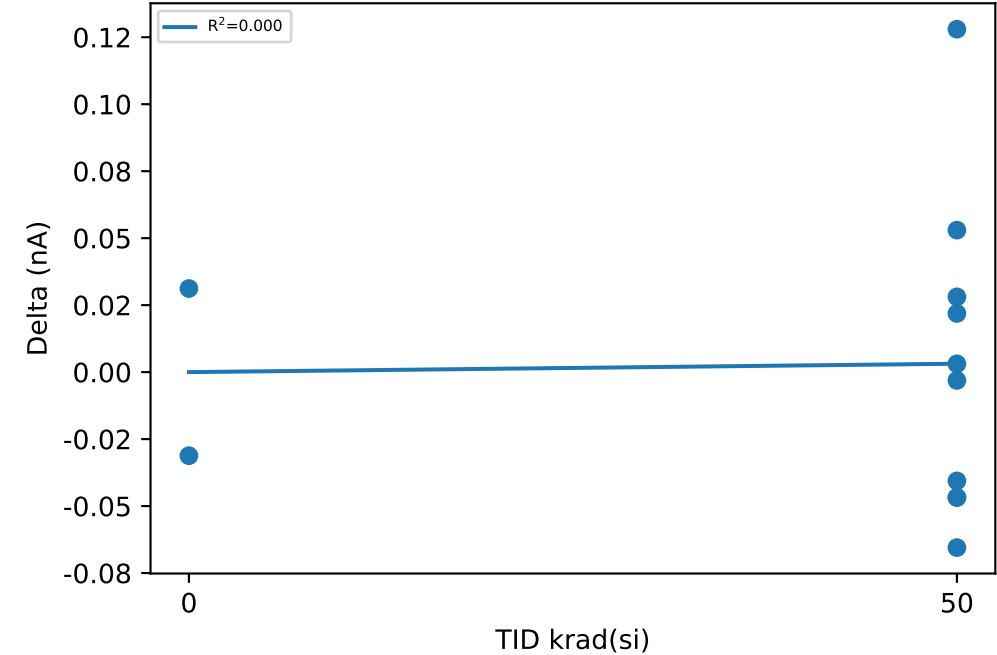
TID vs Result Stats



Test Results (Upper Limit = 25.0 (nA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	-0.0732	-0.042	0.0312
2	0	Correlation	-0.0451	-0.0763	-0.0312
4	50	Bias	-0.0982	-0.0763	0.0219
6	50	Bias	-0.0264	-0.0732	-0.0468
7	50	Bias	-0.0201	-0.0607	-0.0406
8	50	Bias	-0.0888	-0.0919	-0.0031
9	50	Bias	-0.067	-0.1138	-0.0468
11	50	Unbias	-0.0077	-0.0732	-0.0655
12	50	Unbias	-0.0763	-0.0233	0.053
13	50	Unbias	-0.0732	0.0548	0.128
14	50	Unbias	-0.0451	-0.042	0.0031
15	50	Unbias	-0.1325	-0.1044	0.0281

TID vs Post - Pre Exposure Delta

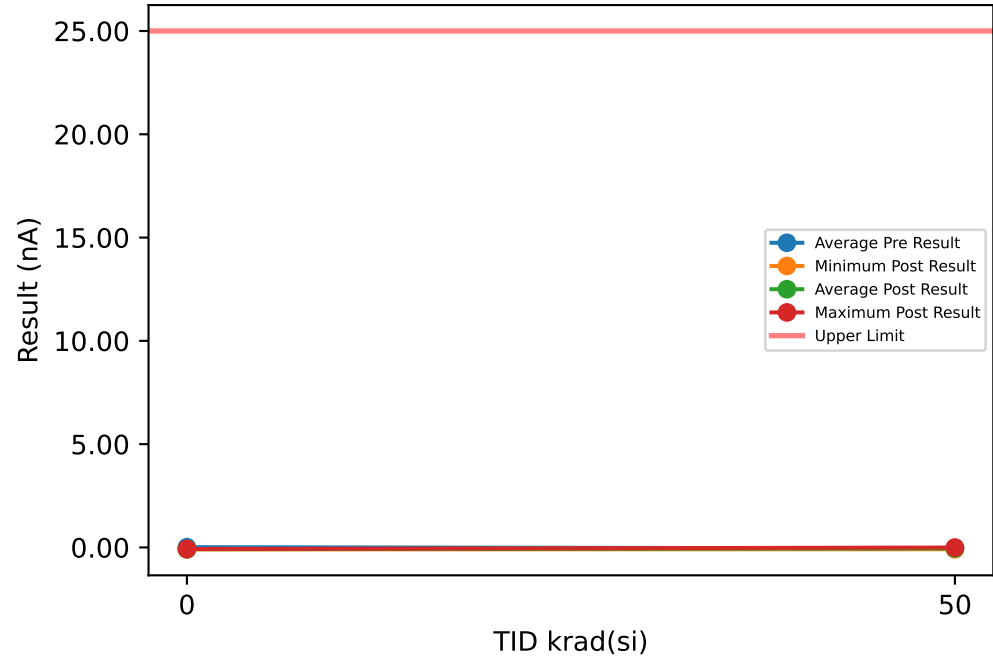


Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.0732	-0.05915	-0.0451	0.01987	-0.0763	-0.05915	-0.042	0.024254	-0.0312	6.9389e-18	0.0312	0.044123
50	-0.1325	-0.06353	-0.0077	0.038855	-0.1138	-0.0604	0.0548	0.048701	-0.0655	0.00313	0.128	0.058407

Device Test: 19.21 EA_IB(CURRENT|EA//12/12/0/0/5/100kHz//@EA_IB)

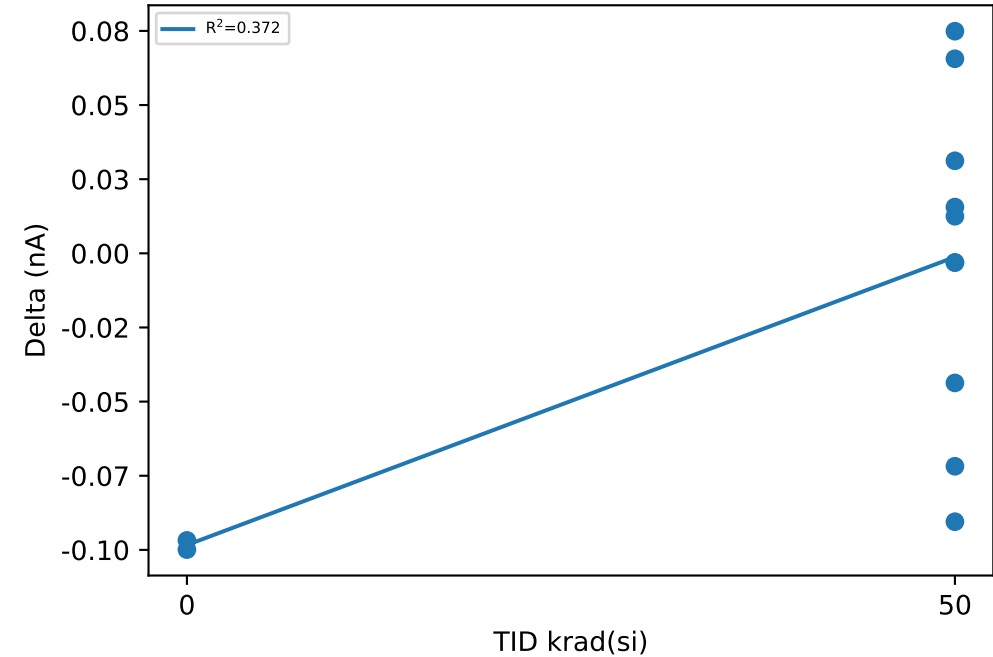
TID vs Result Stats



Test Results (Upper Limit = 25.0 (nA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.0017	-0.0951	-0.0968
2	0	Correlation	0.0236	-0.0763	-0.0999
4	50	Bias	-0.067	-0.0545	0.0125
6	50	Bias	-0.0389	-0.042	-0.0031
7	50	Bias	-0.1138	-0.0389	0.0749
8	50	Bias	-0.0045	-0.0482	-0.0437
9	50	Bias	-0.042	-0.0264	0.0156
11	50	Unbias	0.0048	-0.0857	-0.0905
12	50	Unbias	-0.017	-0.0888	-0.0718
13	50	Unbias	-0.0514	-0.0545	-0.0031
14	50	Unbias	-0.0701	-0.0389	0.0312
15	50	Unbias	-0.0701	-0.0045	0.0656

TID vs Post - Pre Exposure Delta

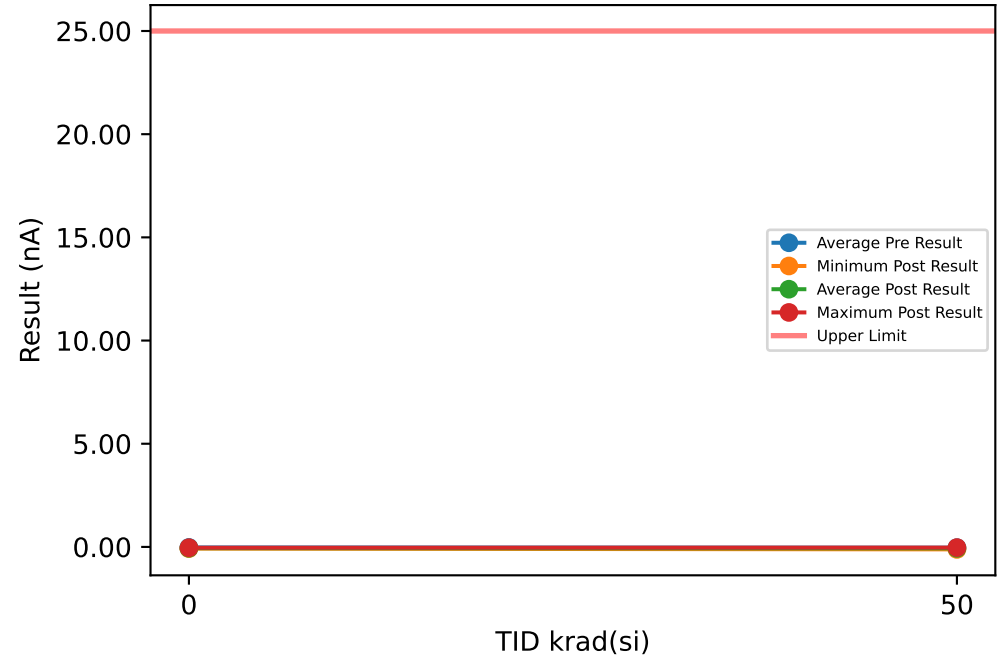


Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0017	0.01265	0.0236	0.015486	-0.0951	-0.0857	-0.0763	0.013294	-0.0999	-0.09835	-0.0968	0.002192
50	-0.1138	-0.047	0.0048	0.035635	-0.0888	-0.04824	-0.0045	0.025233	-0.0905	-0.00124	0.0749	0.054309

Device Test: 19.22 EA_IB(CURRENT|EA//12/12/0/0/5/1MHz//@EA_IB)

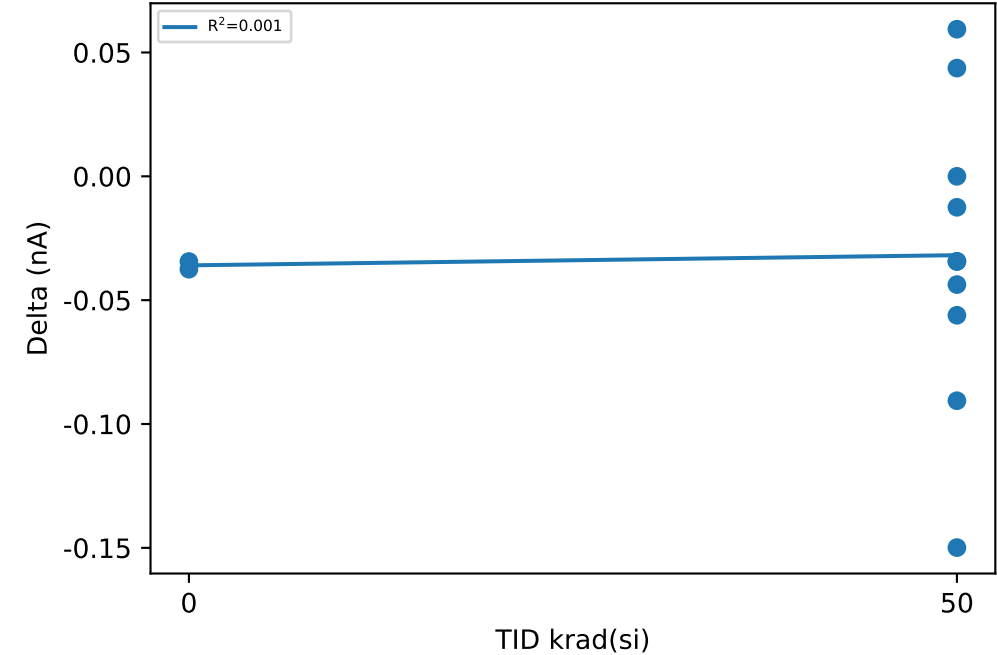
TID vs Result Stats



Test Results (Upper Limit = 25.0 (nA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	-0.0482	-0.0826	-0.0344
2	0	Correlation	-0.0014	-0.0389	-0.0375
4	50	Bias	-0.0358	-0.0358	0
6	50	Bias	-0.0201	-0.1107	-0.0906
7	50	Bias	-0.0826	-0.0389	0.0437
8	50	Bias	-0.1076	-0.0482	0.0594
9	50	Bias	-0.0389	-0.0826	-0.0437
11	50	Unbias	-0.0545	-0.0888	-0.0343
12	50	Unbias	-0.0201	-0.0326	-0.0125
13	50	Unbias	-0.0639	-0.12	-0.0561
14	50	Unbias	-0.0295	-0.0639	-0.0344
15	50	Unbias	0.086	-0.0639	-0.1499

TID vs Post - Pre Exposure Delta

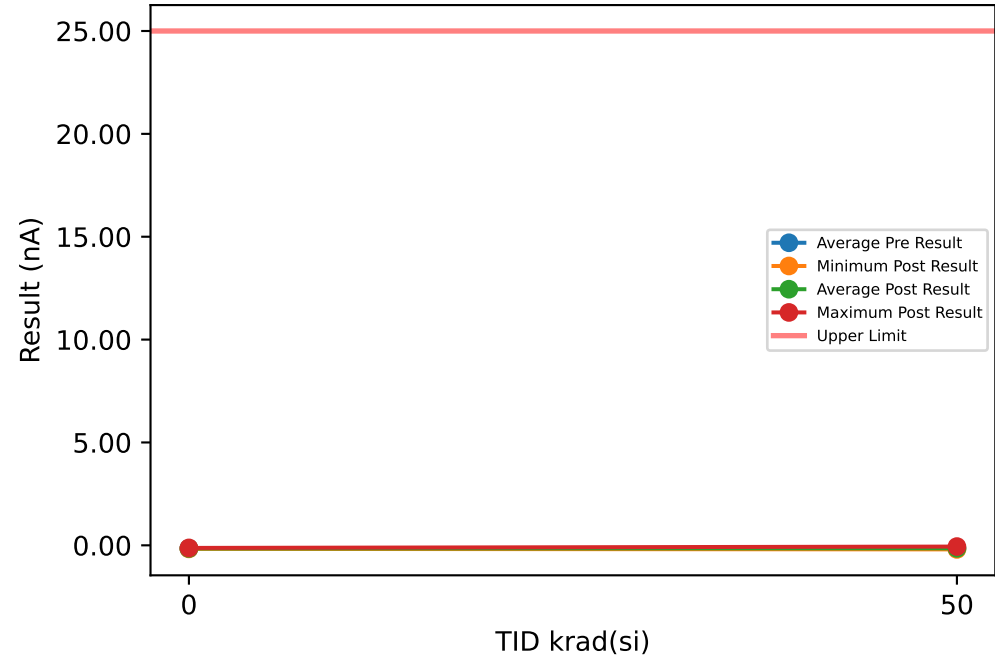


Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.0482	-0.0248	-0.0014	0.033093	-0.0826	-0.06075	-0.0389	0.030901	-0.0375	-0.03595	-0.0344	0.002192
50	-0.1076	-0.0367	0.086	0.051483	-0.12	-0.06854	-0.0326	0.03115	-0.1499	-0.03184	0.0594	0.061057

Device Test: 19.23 EA_IB(CURRENT|EA//14/14/0/0/5/100kHz//@EA_IB)

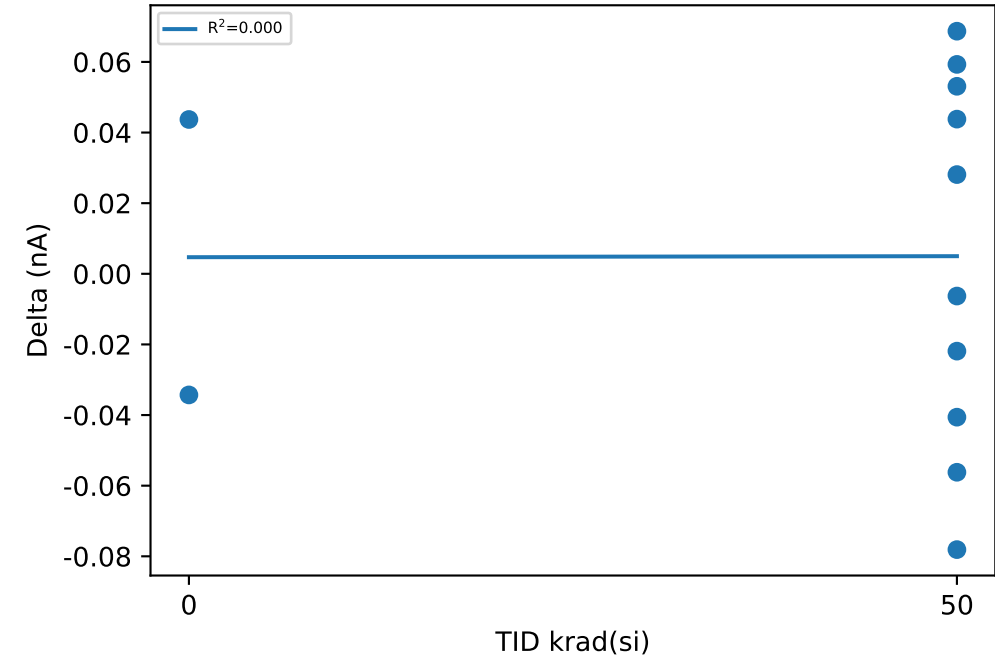
TID vs Result Stats



Test Results (Upper Limit = 25.0 (nA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	-0.17	-0.1263	0.0437
2	0	Correlation	-0.1388	-0.1731	-0.0343
4	50	Bias	-0.1669	-0.1388	0.0281
6	50	Bias	-0.1325	-0.1731	-0.0406
7	50	Bias	-0.1794	-0.1263	0.0531
8	50	Bias	-0.1169	-0.1731	-0.0562
9	50	Bias	-0.1606	-0.1669	-0.0063
11	50	Unbias	-0.2231	-0.1638	0.0593
12	50	Unbias	-0.145	-0.1669	-0.0219
13	50	Unbias	-0.12	-0.1981	-0.0781
14	50	Unbias	-0.1357	-0.0919	0.0438
15	50	Unbias	-0.1294	-0.0607	0.0687

TID vs Post - Pre Exposure Delta

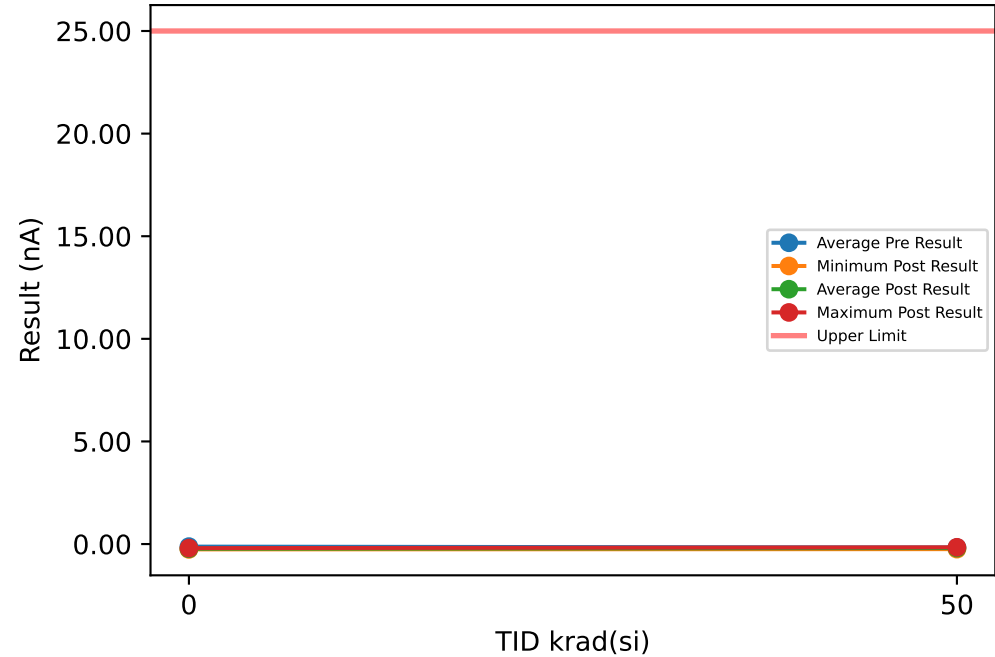


Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.17	-0.1544	-0.1388	0.022062	-0.1731	-0.1497	-0.1263	0.033093	-0.0343	0.0047	0.0437	0.055154
50	-0.2231	-0.15095	-0.1169	0.032579	-0.1981	-0.14596	-0.0607	0.042185	-0.0781	0.00499	0.0687	0.052642

Device Test: 19.24 EA_IB(CURRENT|EA//14/14/0/0/5/1MHz//@EA_IB)

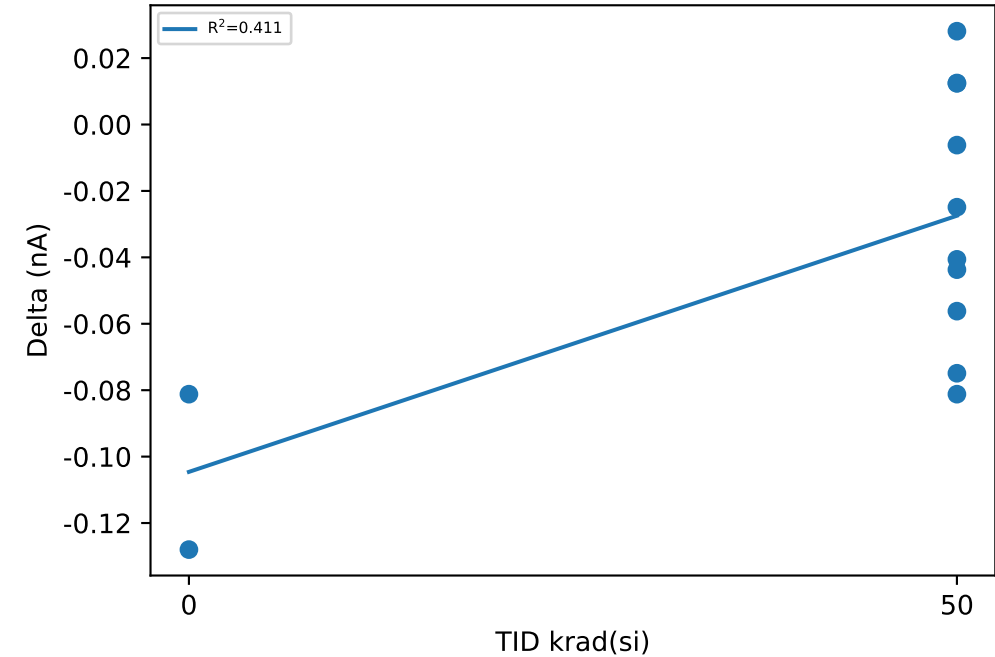
TID vs Result Stats



Test Results (Upper Limit = 25.0 (nA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	-0.1325	-0.2605	-0.128
2	0	Correlation	-0.1169	-0.1981	-0.0812
4	50	Bias	-0.1981	-0.2043	-0.0062
6	50	Bias	-0.1669	-0.2231	-0.0562
7	50	Bias	-0.1263	-0.2075	-0.0812
8	50	Bias	-0.1794	-0.22	-0.0406
9	50	Bias	-0.2231	-0.248	-0.0249
11	50	Unbias	-0.1169	-0.1606	-0.0437
12	50	Unbias	-0.1794	-0.1669	0.0125
13	50	Unbias	-0.1856	-0.1575	0.0281
14	50	Unbias	-0.1388	-0.2137	-0.0749
15	50	Unbias	-0.1762	-0.1638	0.0124

TID vs Post - Pre Exposure Delta

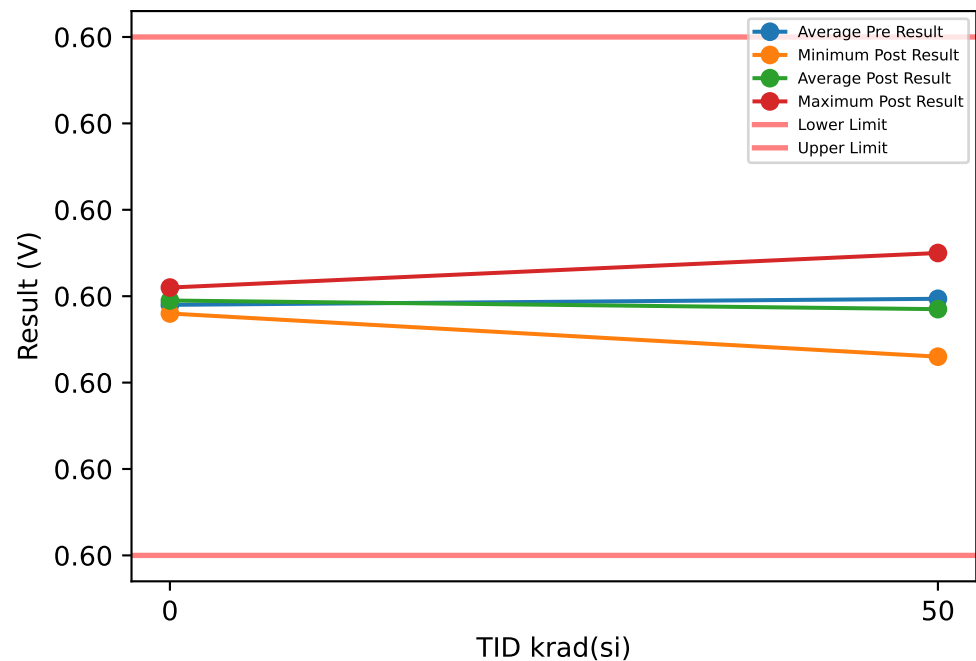


Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.1325	-0.1247	-0.1169	0.011031	-0.2605	-0.2293	-0.1981	0.044123	-0.128	-0.1046	-0.0812	0.033093
50	-0.2231	-0.16907	-0.1169	0.03295	-0.248	-0.19654	-0.1575	0.031876	-0.0812	-0.02747	0.0281	0.038198

Device Test: 19.25 VREF_25C(VOLTAGE|VREF//4.5/4.5/0/0/4.5/100kHz//@VREF_25C)

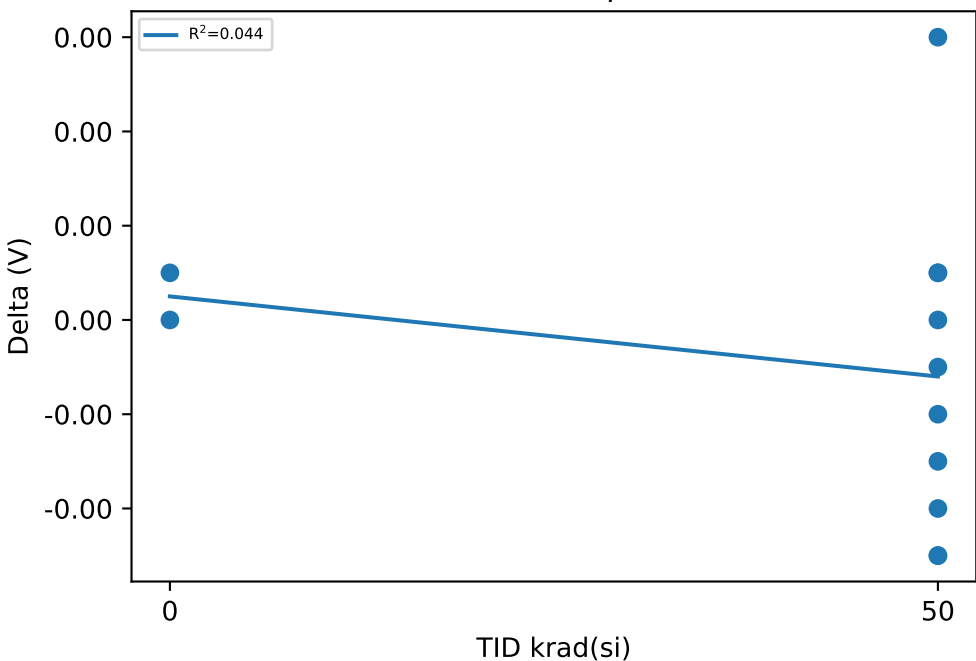
TID vs Result Stats



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5998	0.5998	0
2	0	Correlation	0.6	0.6001	0.0001
4	50	Bias	0.5998	0.5993	-0.0005
6	50	Bias	0.5998	0.5993	-0.0005
7	50	Bias	0.6003	0.6003	0
8	50	Bias	0.5999	0.5997	-0.0002
9	50	Bias	0.5999	0.5996	-0.0003
11	50	Unbias	0.6001	0.6002	0.0001
12	50	Unbias	0.6002	0.6003	0.0001
13	50	Unbias	0.6001	0.6	-0.0001
14	50	Unbias	0.5997	0.5993	-0.0004
15	50	Unbias	0.5999	0.6005	0.0006

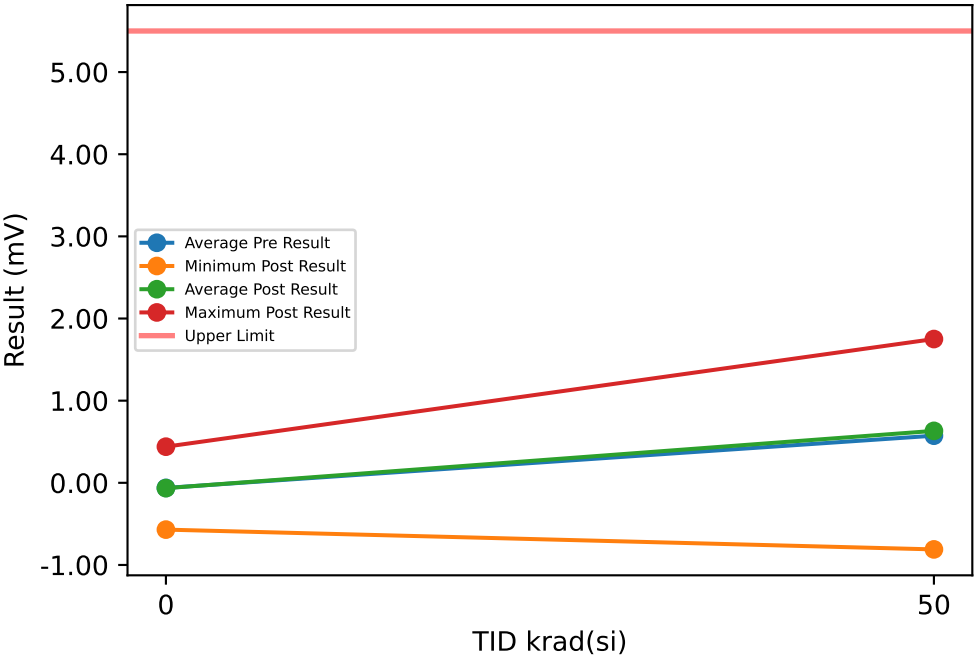
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5998	0.5999	0.6	0.00014142	0.5998	0.59995	0.6001	0.00021213	0	5e-05	0.0001	7.0711e-05
50	0.5997	0.59997	0.6003	0.00019465	0.5993	0.59985	0.6005	0.00046726	-0.0005	-0.00012	0.0006	0.00033928

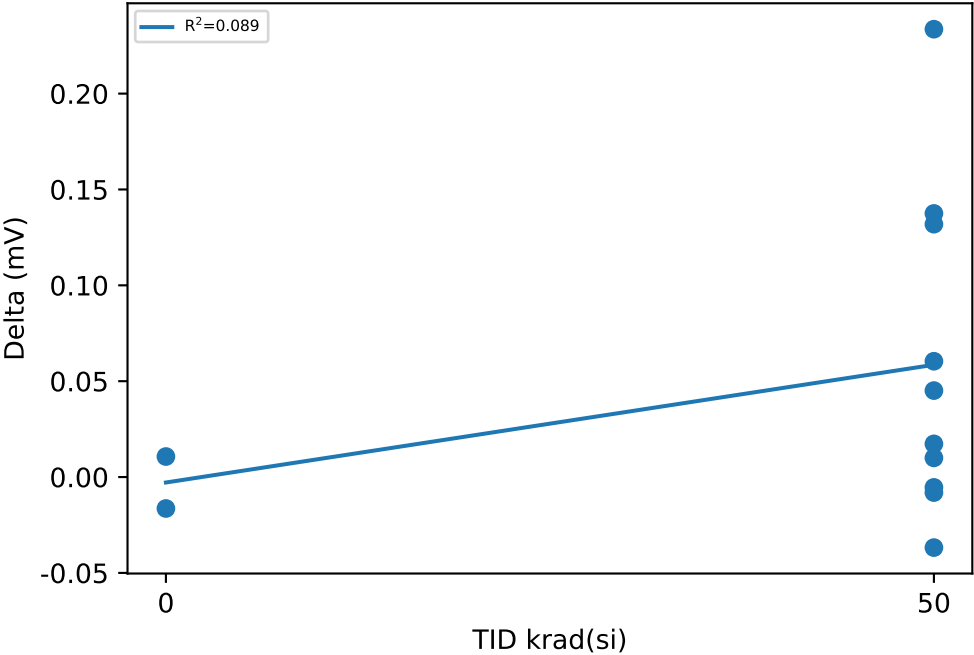
TID vs Result Stats



Test Results (Upper Limit = 5.5 (mV))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.4562	0.4398	-0.0164
2	0	Correlation	-0.5804	-0.5697	0.0107
4	50	Bias	0.1336	0.2655	0.1319
6	50	Bias	0.6077	0.5709	-0.0368
7	50	Bias	-0.2101	-0.1497	0.0604
8	50	Bias	0.0778	0.2153	0.1375
9	50	Bias	-0.8278	-0.8105	0.0173
11	50	Unbias	1.0548	1.0648	0.01
12	50	Unbias	1.5166	1.7502	0.2336
13	50	Unbias	1.4666	1.4585	-0.0081
14	50	Unbias	0.7494	0.744	-0.0054
15	50	Unbias	1.1678	1.2129	0.0451

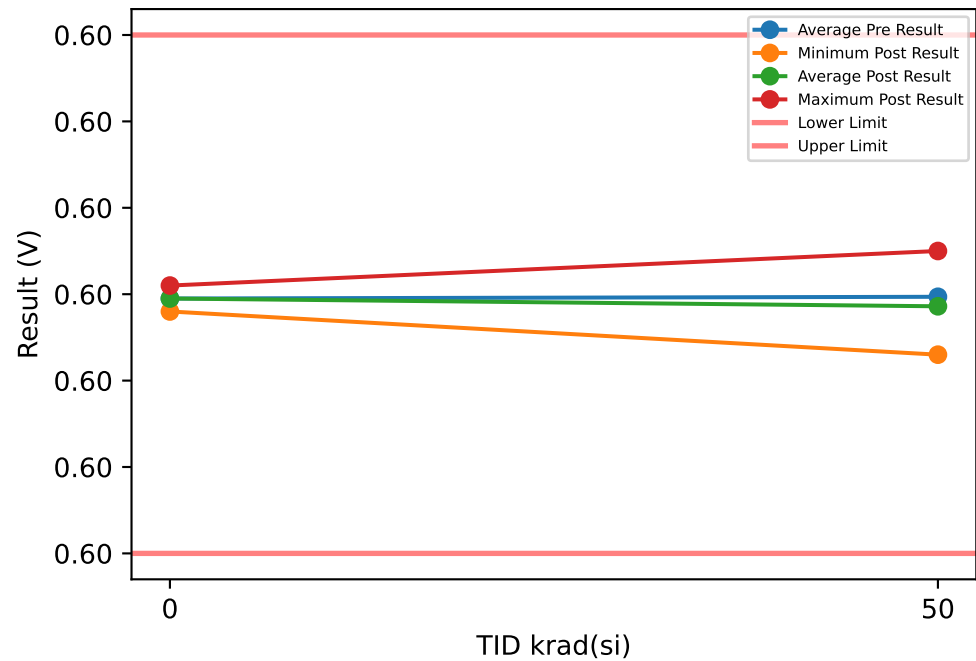
TID vs Post - Pre Exposure Delta



Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.5804	-0.0621	0.4562	0.73299	-0.5697	-0.06495	0.4398	0.71382	-0.0164	-0.00285	0.0107	0.019163
50	-0.8278	0.57364	1.5166	0.7689	-0.8105	0.63219	1.7502	0.77991	-0.0368	0.05855	0.2336	0.084408

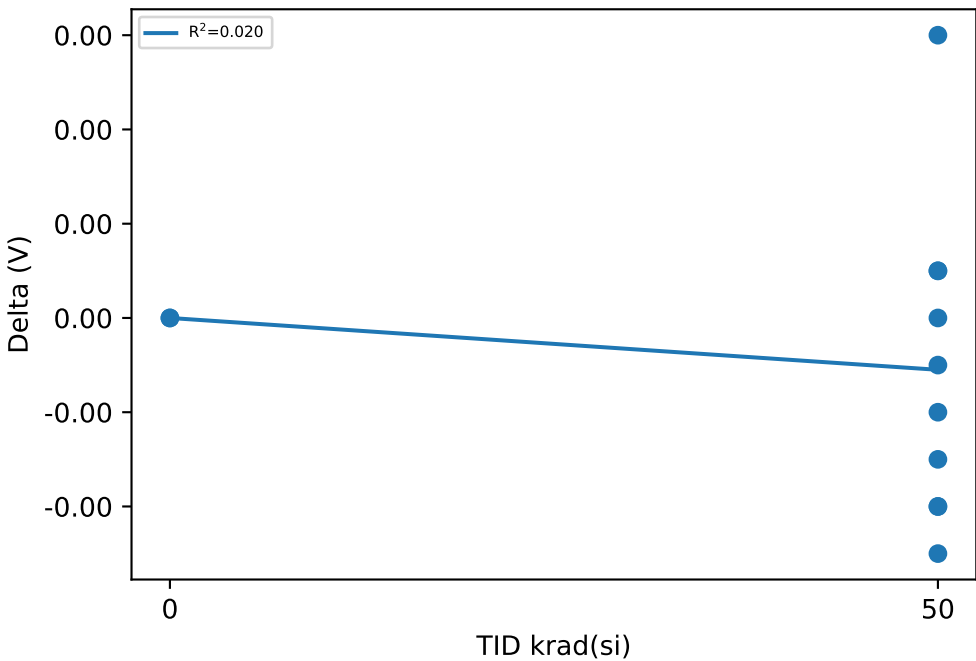
TID vs Result Stats



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5998	0.5998	0
2	0	Correlation	0.6001	0.6001	0
4	50	Bias	0.5998	0.5993	-0.0005
6	50	Bias	0.5998	0.5994	-0.0004
7	50	Bias	0.6003	0.6003	0
8	50	Bias	0.5999	0.5997	-0.0002
9	50	Bias	0.5999	0.5996	-0.0003
11	50	Unbias	0.6001	0.6002	0.0001
12	50	Unbias	0.6002	0.6003	0.0001
13	50	Unbias	0.6001	0.6	-0.0001
14	50	Unbias	0.5997	0.5993	-0.0004
15	50	Unbias	0.5999	0.6005	0.0006

TID vs Post - Pre Exposure Delta

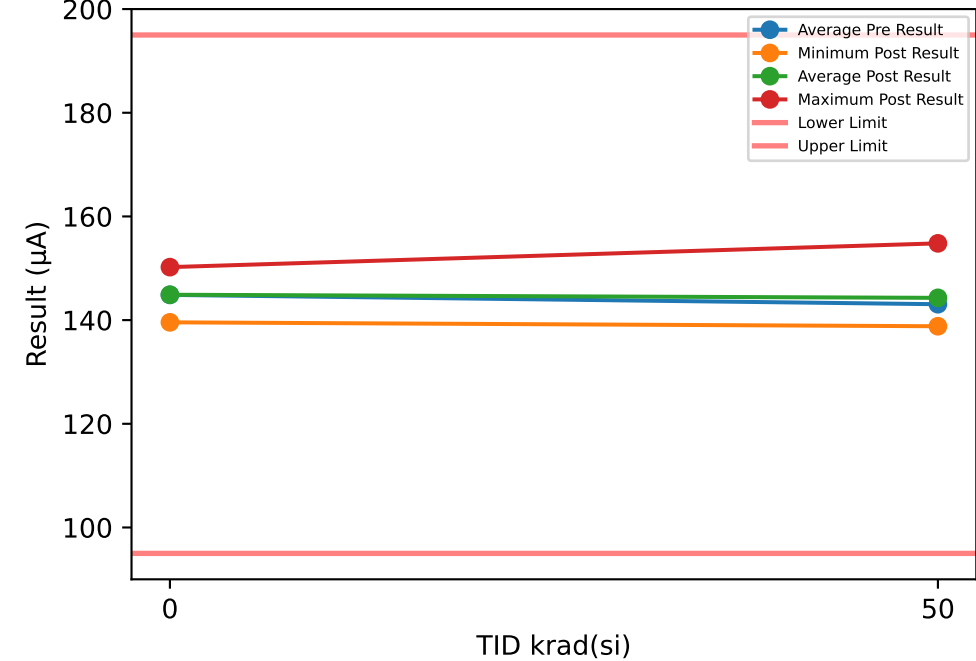


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5998	0.59995	0.6001	0.00021213	0.5998	0.59995	0.6001	0.00021213	0	0	0	0
50	0.5997	0.59997	0.6003	0.00019465	0.5993	0.59986	0.6005	0.00045509	-0.0005	-0.00011	0.0006	0.00032813

Device Test: 19.3 EA_I_SINK(CURRENT|EA_SINK//4.5/4.5/0/0/4.5/500kHz//@EA_I_SINK)

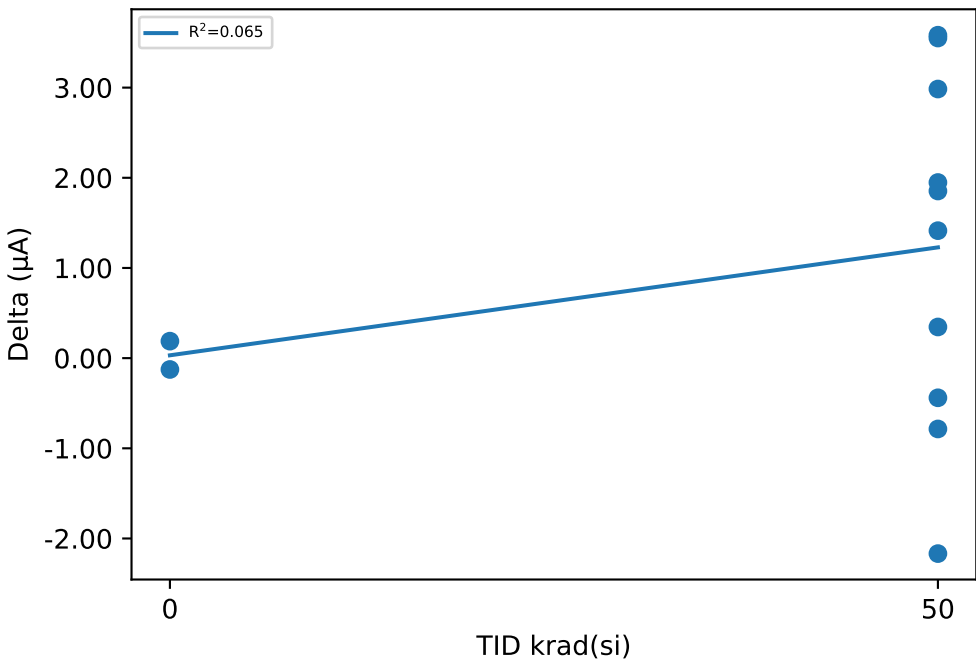
TID vs Result Stats



Test Results (Lower Limit = 95.0, Upper Limit = 195.0 (µA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	150.35	150.22	-0.1257
2	0	Correlation	139.38	139.57	0.1884
4	50	Bias	142.08	143.94	1.8535
6	50	Bias	149.47	147.3	-2.1676
7	50	Bias	138.47	138.82	0.3456
8	50	Bias	143	145.98	2.9844
9	50	Bias	143.28	142.84	-0.4398
11	50	Unbias	141.83	143.25	1.4137
12	50	Unbias	140.95	140.17	-0.7854
13	50	Unbias	142.56	146.11	3.5499
14	50	Unbias	137.81	139.76	1.9477
15	50	Unbias	151.23	154.81	3.5813

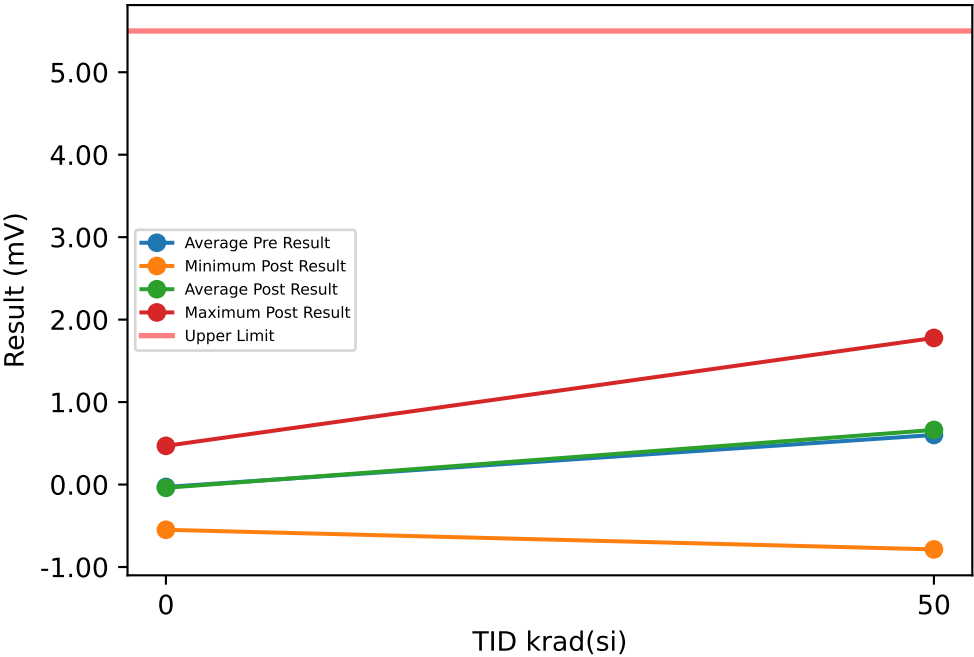
TID vs Post - Pre Exposure Delta



Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	139.38	144.86	150.35	7.7525	139.57	144.9	150.22	7.5304	-0.1257	0.03135	0.1884	0.2221
50	137.81	143.07	151.23	4.2626	138.82	144.3	154.81	4.6739	-2.1676	1.2283	3.5813	1.9466

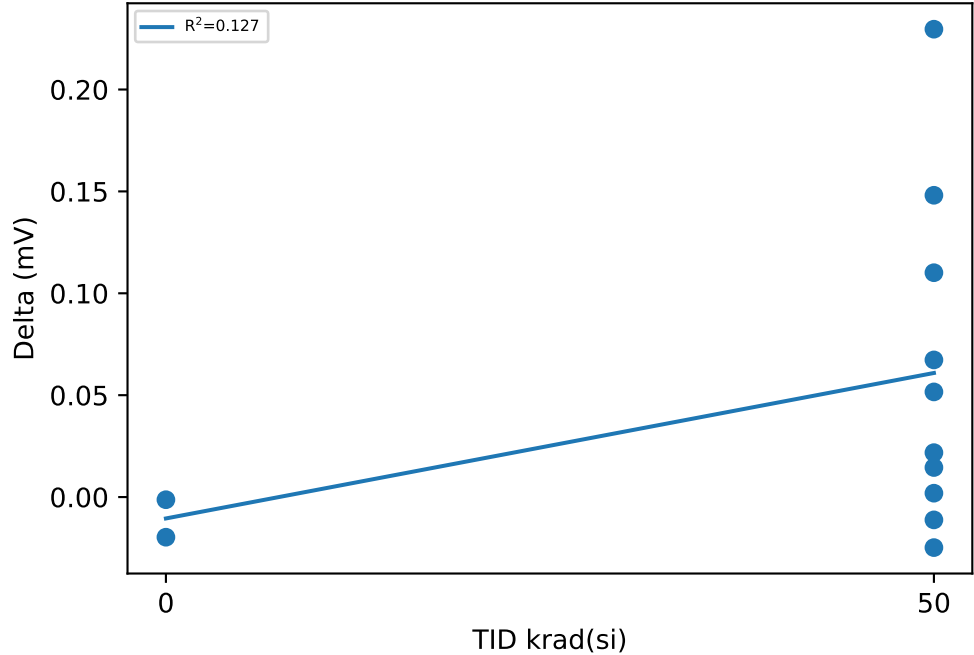
TID vs Result Stats



Test Results (Upper Limit = 5.5 (mV))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.4889	0.4692	-0.0197
2	0	Correlation	-0.547	-0.5483	-0.0013
4	50	Bias	0.177	0.2871	0.1101
6	50	Bias	0.6355	0.6107	-0.0248
7	50	Bias	-0.1885	-0.1212	0.0673
8	50	Bias	0.1022	0.2503	0.1481
9	50	Bias	-0.8008	-0.7863	0.0145
11	50	Unbias	1.065	1.0868	0.0218
12	50	Unbias	1.5483	1.7779	0.2296
13	50	Unbias	1.4898	1.4917	0.0019
14	50	Unbias	0.783	0.7718	-0.0112
15	50	Unbias	1.2025	1.2541	0.0516

TID vs Post - Pre Exposure Delta

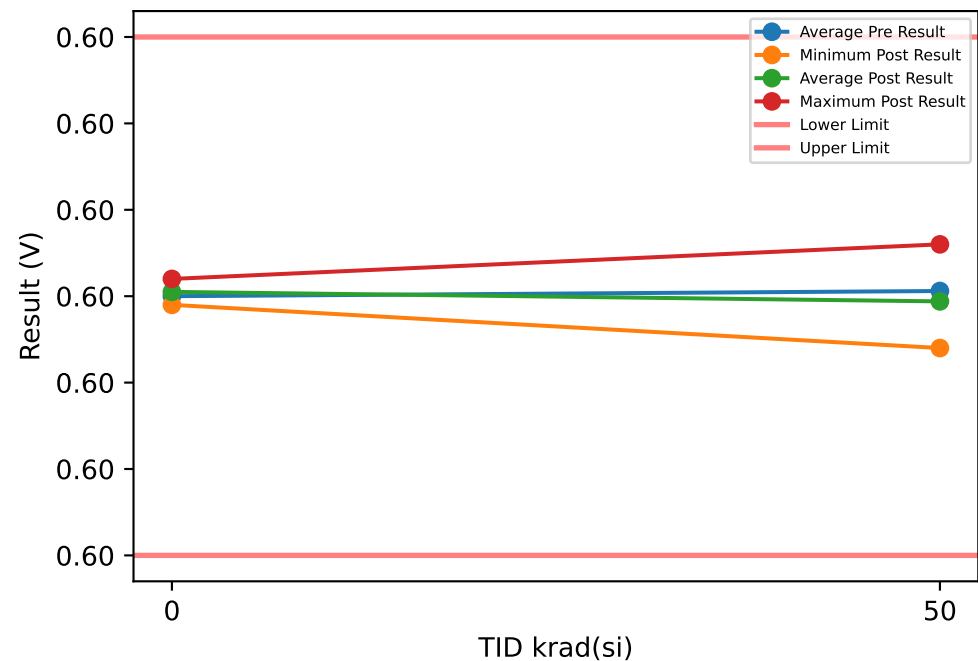


Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.547	-0.02905	0.4889	0.73249	-0.5483	-0.03955	0.4692	0.71948	-0.0197	-0.0105	-0.0013	0.013011
50	-0.8008	0.6014	1.5483	0.76853	-0.7863	0.66229	1.7779	0.78176	-0.0248	0.06089	0.2296	0.080497

Device Test: 19.31 VREF_25C(VOLTAGE|VREF//12/12/0/0/5/100kHz//@VREF_25C)

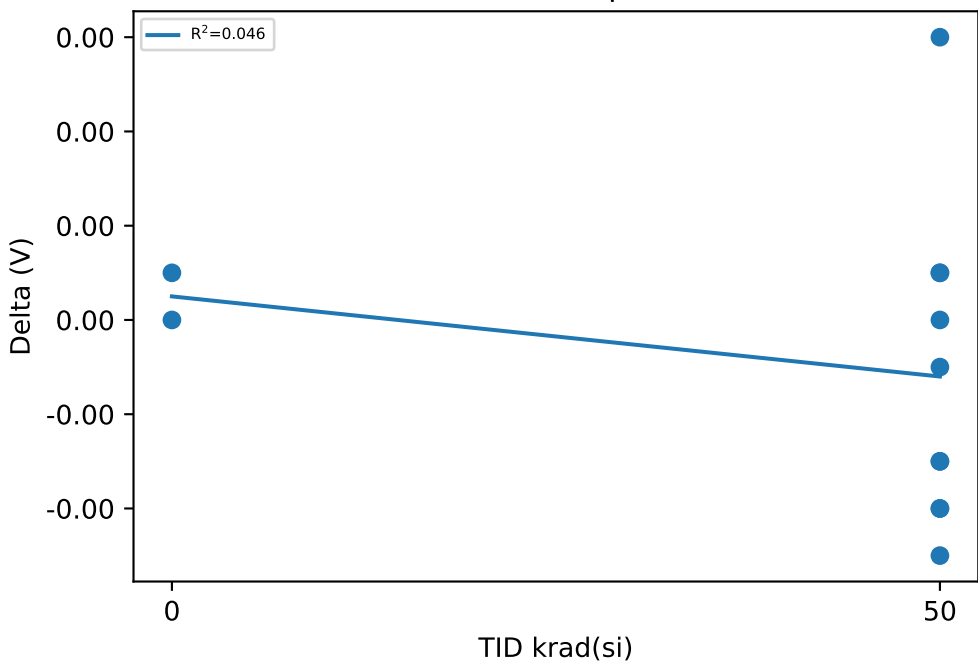
TID vs Result Stats



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5999	0.5999	0
2	0	Correlation	0.6001	0.6002	0.0001
4	50	Bias	0.5998	0.5994	-0.0004
6	50	Bias	0.5999	0.5994	-0.0005
7	50	Bias	0.6004	0.6004	0
8	50	Bias	0.6	0.5997	-0.0003
9	50	Bias	0.6	0.5997	-0.0003
11	50	Unbias	0.6002	0.6003	0.0001
12	50	Unbias	0.6003	0.6004	0.0001
13	50	Unbias	0.6002	0.6001	-0.0001
14	50	Unbias	0.5998	0.5994	-0.0004
15	50	Unbias	0.6	0.6006	0.0006

TID vs Post - Pre Exposure Delta

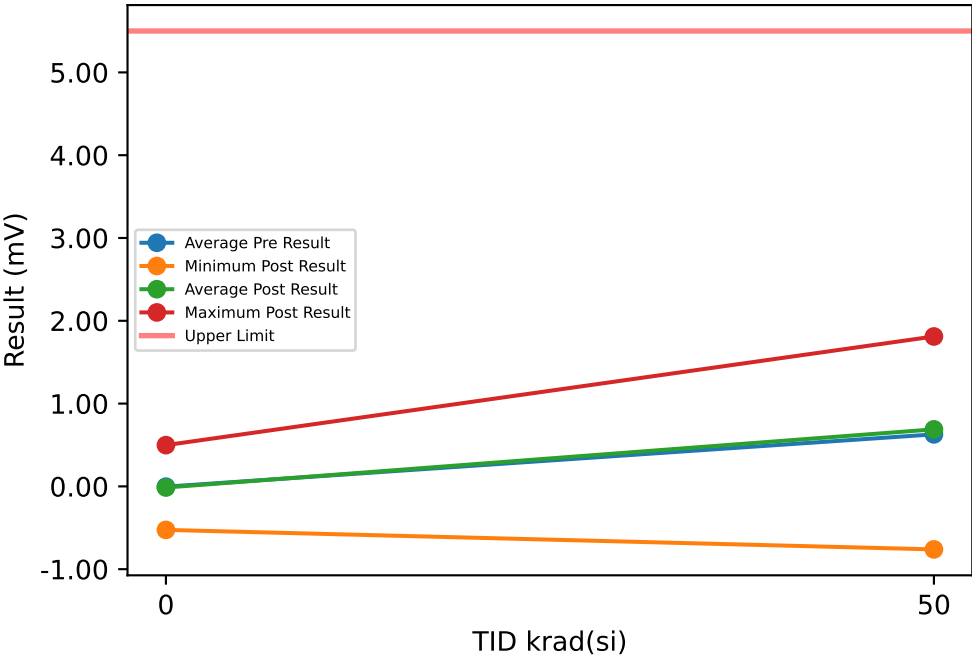


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5999	0.6	0.6001	0.00014142	0.5999	0.60005	0.6002	0.00021213	0	5e-05	0.0001	7.0711e-05
50	0.5998	0.60006	0.6004	0.00020656	0.5994	0.59994	0.6006	0.00047188	-0.0005	-0.00012	0.0006	0.00033267

Device Test: 19.33 EA_OS(VOLTAGE|OFFSET//12/12/0/0/5/100kHz//@EA_OS)

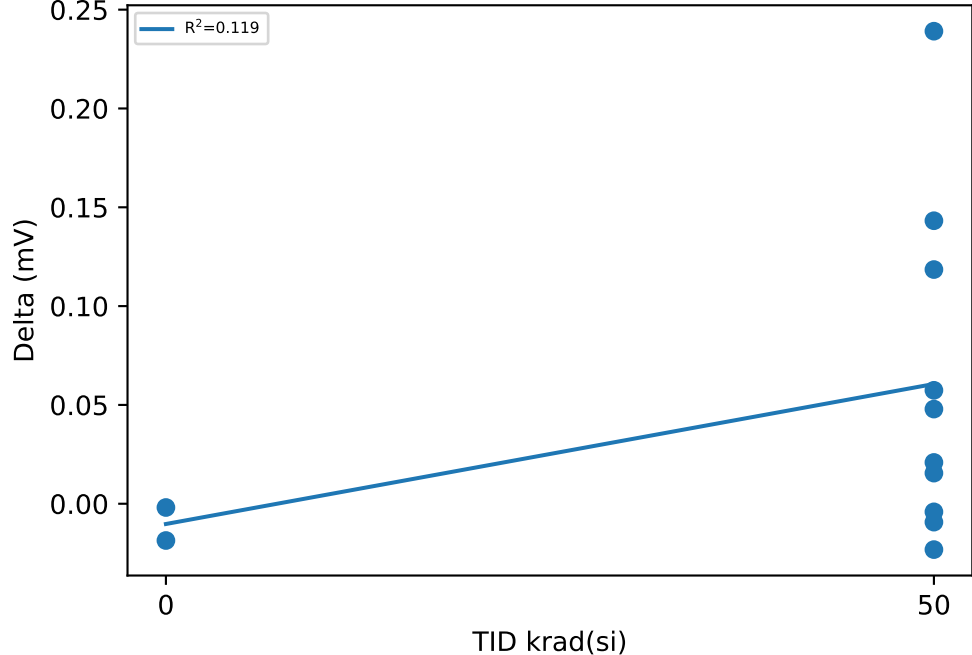
TID vs Result Stats



Test Results (Upper Limit = 5.5 (mV))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5169	0.4983	-0.0186
2	0	Correlation	-0.5235	-0.5254	-0.0019
4	50	Bias	0.1963	0.3148	0.1185
6	50	Bias	0.6603	0.6371	-0.0232
7	50	Bias	-0.1566	-0.0992	0.0574
8	50	Bias	0.1308	0.274	0.1432
9	50	Bias	-0.7765	-0.761	0.0155
11	50	Unbias	1.0966	1.1175	0.0209
12	50	Unbias	1.5715	1.8106	0.2391
13	50	Unbias	1.5217	1.5176	-0.0041
14	50	Unbias	0.8041	0.7948	-0.0093
15	50	Unbias	1.2345	1.2824	0.0479

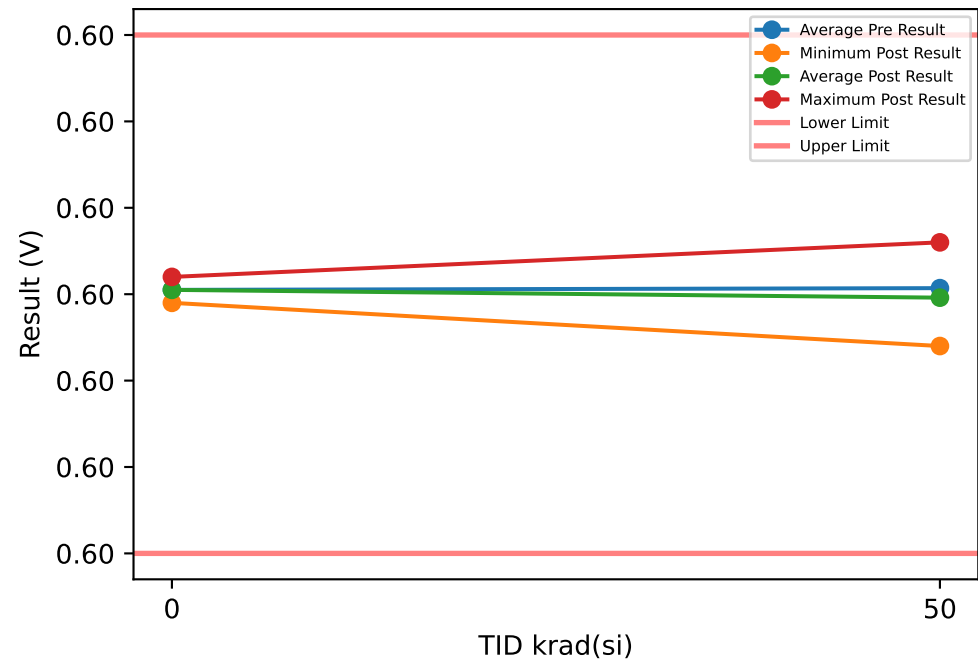
TID vs Post - Pre Exposure Delta



Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.5235	-0.0033	0.5169	0.73567	-0.5254	-0.01355	0.4983	0.72387	-0.0186	-0.01025	-0.0019	0.011809
50	-0.7765	0.62827	1.5715	0.76957	-0.761	0.68886	1.8106	0.78388	-0.0232	0.06059	0.2391	0.082941

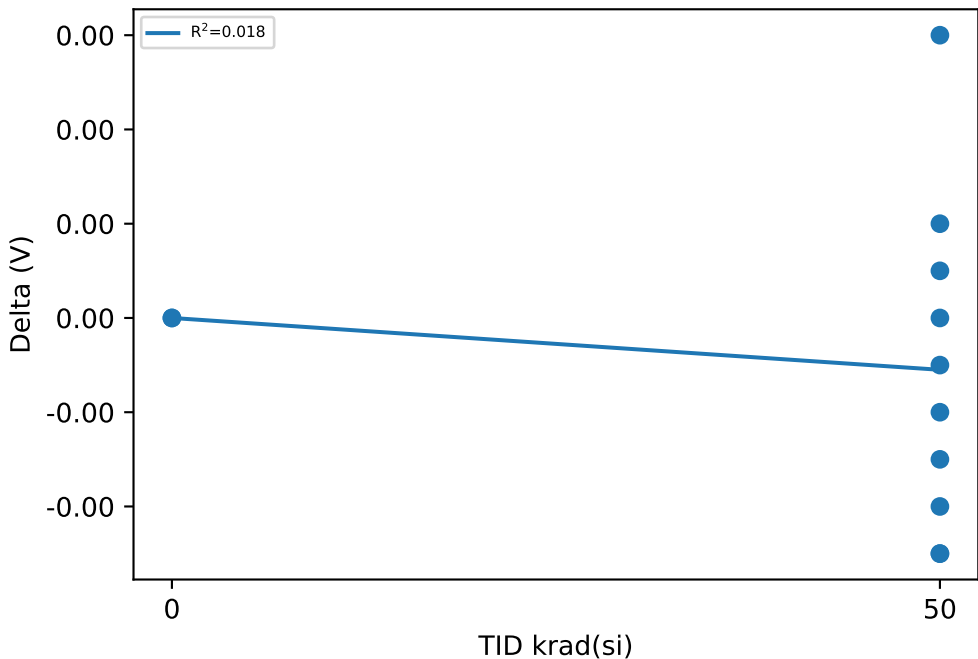
TID vs Result Stats



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5999	0.5999	0
2	0	Correlation	0.6002	0.6002	0
4	50	Bias	0.5999	0.5994	-0.0005
6	50	Bias	0.5999	0.5994	-0.0005
7	50	Bias	0.6004	0.6004	0
8	50	Bias	0.6	0.5998	-0.0002
9	50	Bias	0.6	0.5997	-0.0003
11	50	Unbias	0.6002	0.6004	0.0002
12	50	Unbias	0.6003	0.6004	0.0001
13	50	Unbias	0.6002	0.6001	-0.0001
14	50	Unbias	0.5998	0.5994	-0.0004
15	50	Unbias	0.6	0.6006	0.0006

TID vs Post - Pre Exposure Delta

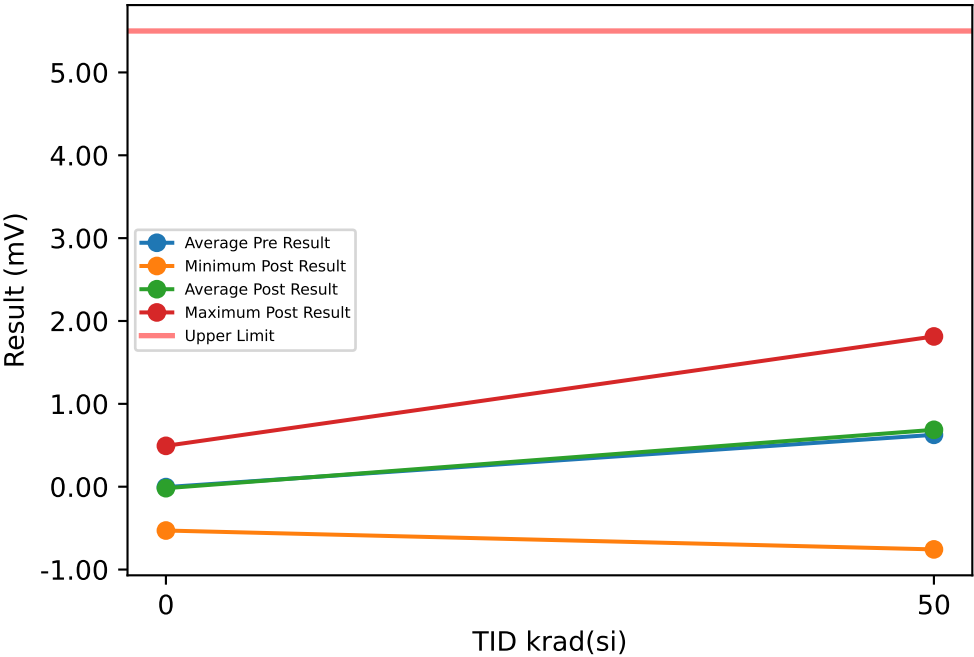


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5999	0.60005	0.6002	0.00021213	0.5999	0.60005	0.6002	0.00021213	0	0	0	0
50	0.5998	0.60007	0.6004	0.00019465	0.5994	0.59996	0.6006	0.00047656	-0.0005	-0.00011	0.0006	0.00034785

Device Test: 19.36 EA_OS(VOLTAGE|OFFSET//14/14/0/0/5/100kHz//@EA_OS)

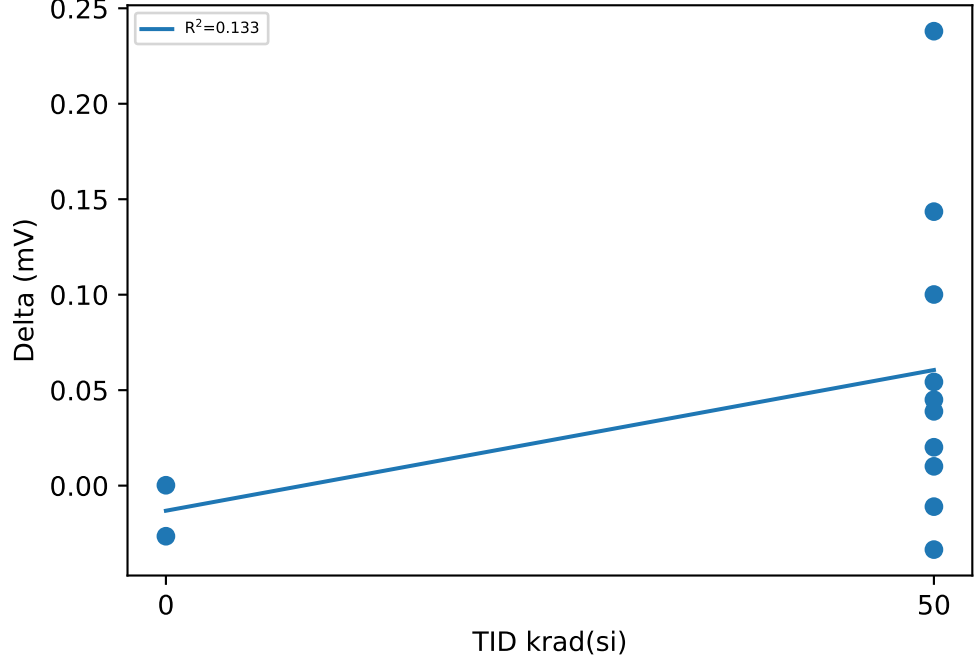
TID vs Result Stats



Test Results (Upper Limit = 5.5 (mV))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5195	0.493	-0.0265
2	0	Correlation	-0.5291	-0.5289	0.0002
4	50	Bias	0.2055	0.3056	0.1001
6	50	Bias	0.66	0.6265	-0.0335
7	50	Bias	-0.1623	-0.108	0.0543
8	50	Bias	0.1265	0.27	0.1435
9	50	Bias	-0.7768	-0.7567	0.0201
11	50	Unbias	1.0876	1.1265	0.0389
12	50	Unbias	1.5755	1.8135	0.238
13	50	Unbias	1.514	1.5241	0.0101
14	50	Unbias	0.8074	0.7964	-0.011
15	50	Unbias	1.2241	1.2691	0.045

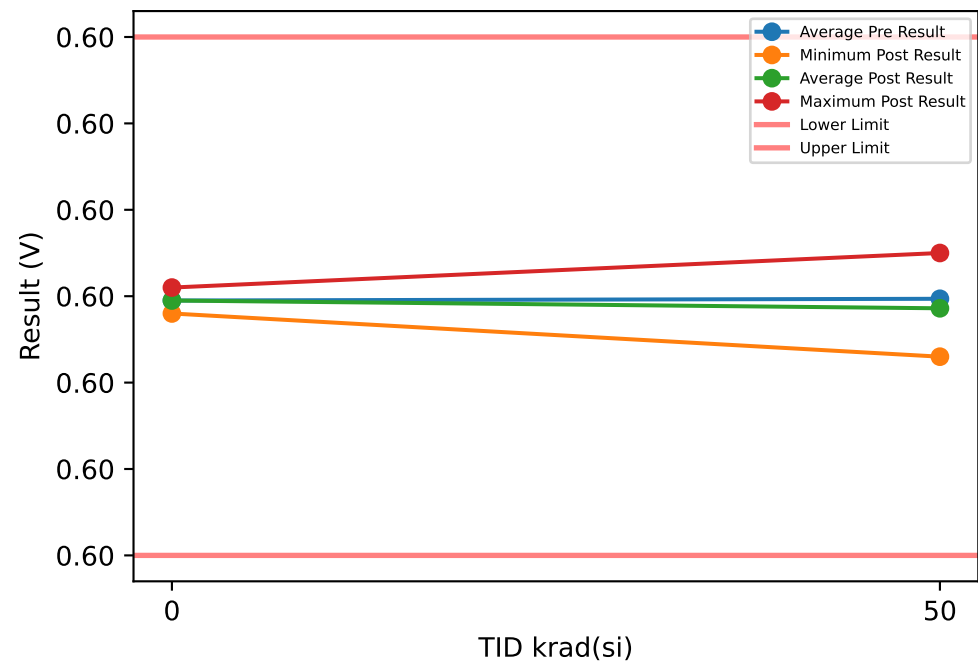
TID vs Post - Pre Exposure Delta



Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.5291	-0.0048	0.5195	0.74147	-0.5289	-0.01795	0.493	0.72259	-0.0265	-0.01315	0.0002	0.01888
50	-0.7768	0.62615	1.5755	0.76815	-0.7567	0.6867	1.8135	0.78549	-0.0335	0.06055	0.238	0.080849

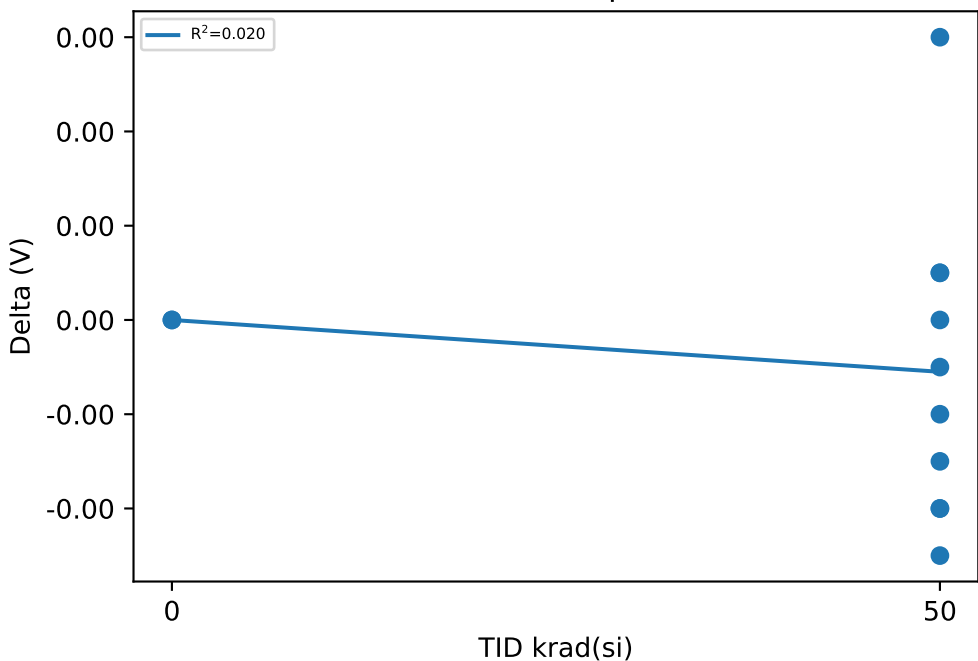
TID vs Result Stats



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5998	0.5998	0
2	0	Correlation	0.6001	0.6001	0
4	50	Bias	0.5998	0.5993	-0.0005
6	50	Bias	0.5998	0.5994	-0.0004
7	50	Bias	0.6003	0.6003	0
8	50	Bias	0.5999	0.5997	-0.0002
9	50	Bias	0.5999	0.5996	-0.0003
11	50	Unbias	0.6001	0.6002	0.0001
12	50	Unbias	0.6002	0.6003	0.0001
13	50	Unbias	0.6001	0.6	-0.0001
14	50	Unbias	0.5997	0.5993	-0.0004
15	50	Unbias	0.5999	0.6005	0.0006

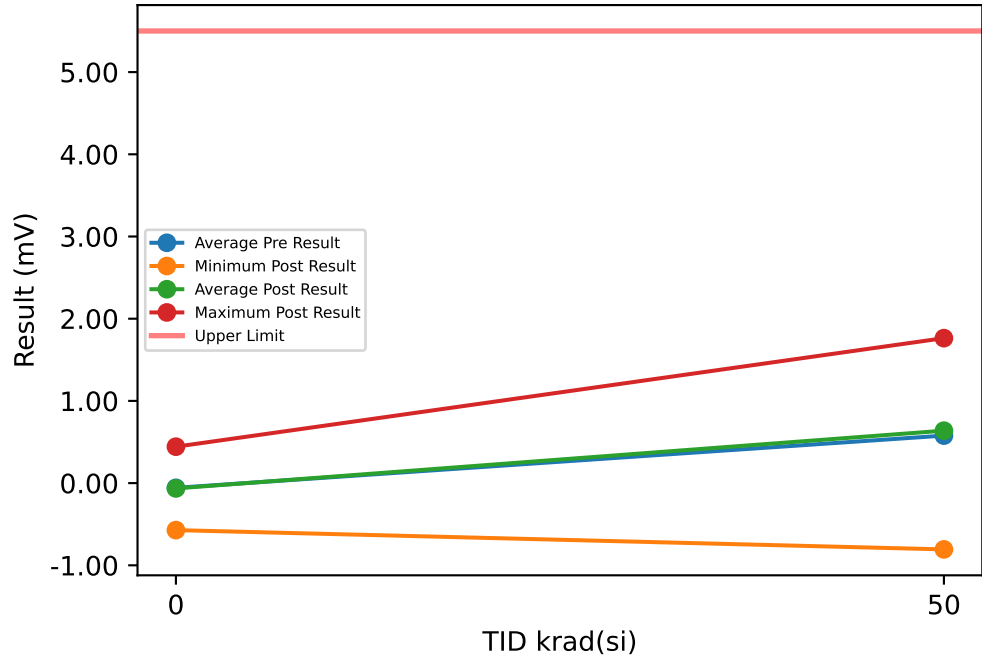
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5998	0.59995	0.6001	0.00021213	0.5998	0.59995	0.6001	0.00021213	0	0	0	0
50	0.5997	0.59997	0.6003	0.00019465	0.5993	0.59986	0.6005	0.00045509	-0.0005	-0.00011	0.0006	0.00032813

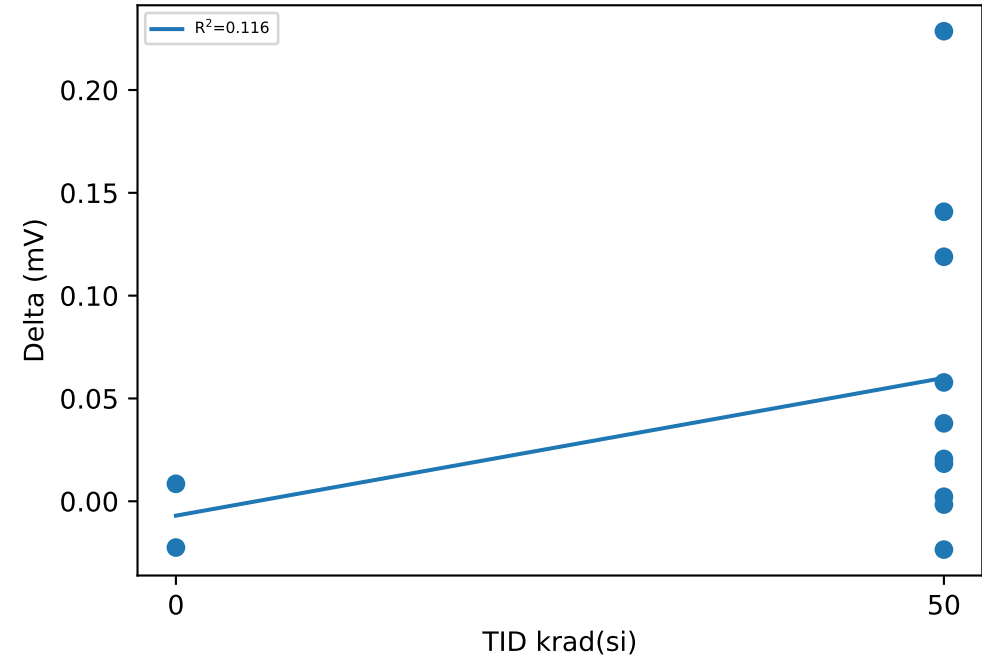
TID vs Result Stats



Test Results (Upper Limit = 5.5 (mV))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.4656	0.4431	-0.0225
2	0	Correlation	-0.5804	-0.5719	0.0085
4	50	Bias	0.1488	0.2677	0.1189
6	50	Bias	0.6113	0.5878	-0.0235
7	50	Bias	-0.2088	-0.151	0.0578
8	50	Bias	0.0834	0.2242	0.1408
9	50	Bias	-0.827	-0.8064	0.0206
11	50	Unbias	1.0417	1.06	0.0183
12	50	Unbias	1.5348	1.7634	0.2286
13	50	Unbias	1.4685	1.4707	0.0022
14	50	Unbias	0.7544	0.7528	-0.0016
15	50	Unbias	1.1718	1.2097	0.0379

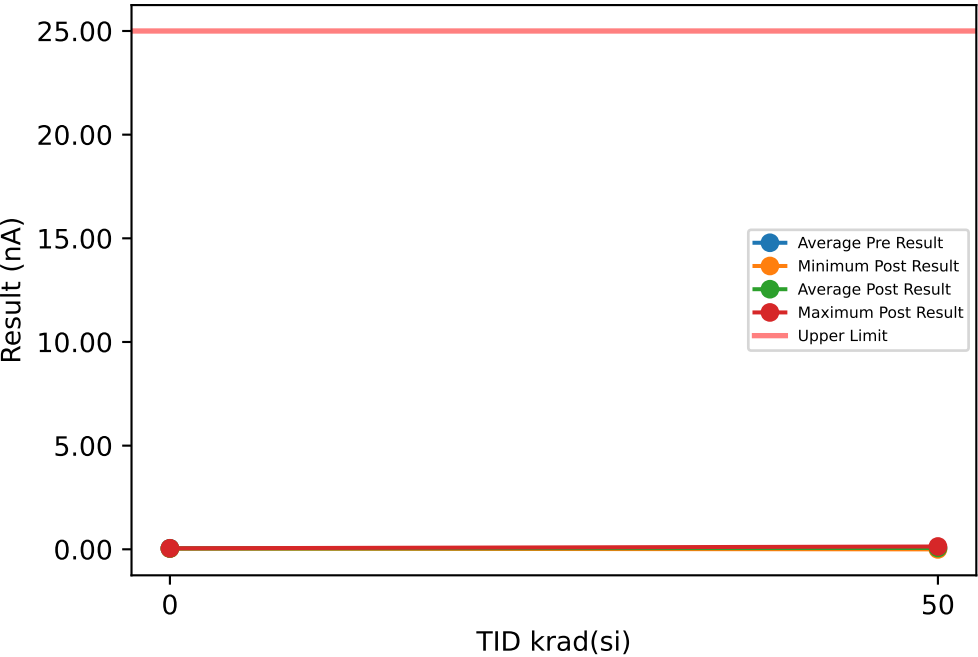
TID vs Post - Pre Exposure Delta



Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.5804	-0.0574	0.4656	0.73963	-0.5719	-0.0644	0.4431	0.71771	-0.0225	-0.007	0.0085	0.02192
50	-0.827	0.57789	1.5348	0.76958	-0.8064	0.63789	1.7634	0.78157	-0.0235	0.06	0.2286	0.079103

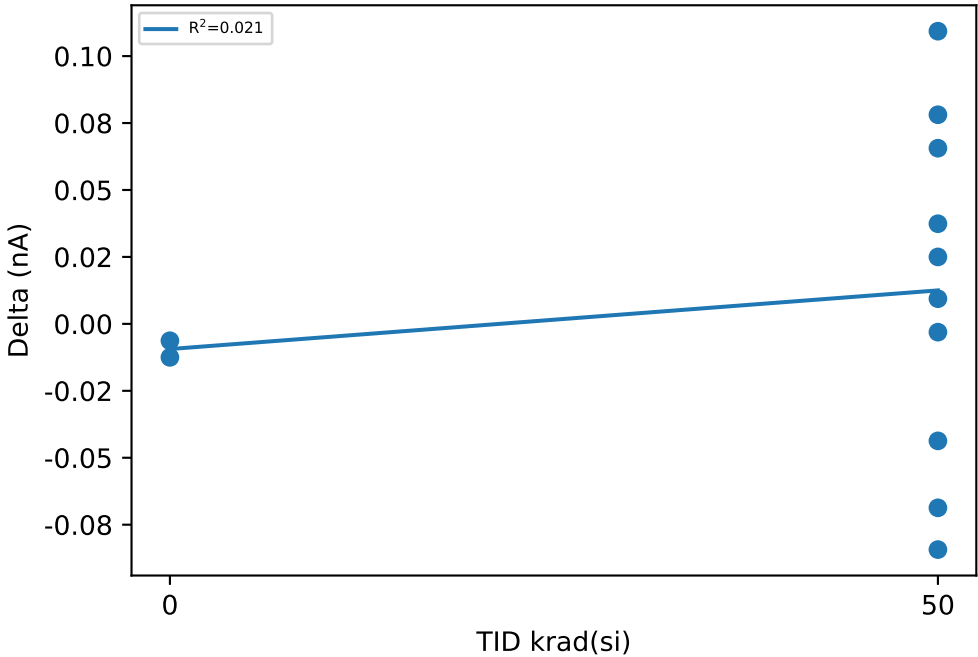
TID vs Result Stats



Test Results (Upper Limit = 25.0 (nA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.0454	0.0329	-0.0125
2	0	Correlation	0.0548	0.0485	-0.0063
4	50	Bias	0.061	0.0579	-0.0031
6	50	Bias	0.0048	0.1141	0.1093
7	50	Bias	0.136	0.0517	-0.0843
8	50	Bias	0.0642	-0.0045	-0.0687
9	50	Bias	0.0579	0.136	0.0781
11	50	Unbias	0.0392	0.0766	0.0374
12	50	Unbias	0.0017	0.0673	0.0656
13	50	Unbias	0.0017	0.0111	0.0094
14	50	Unbias	0.061	0.0173	-0.0437
15	50	Unbias	0.0891	0.1141	0.025

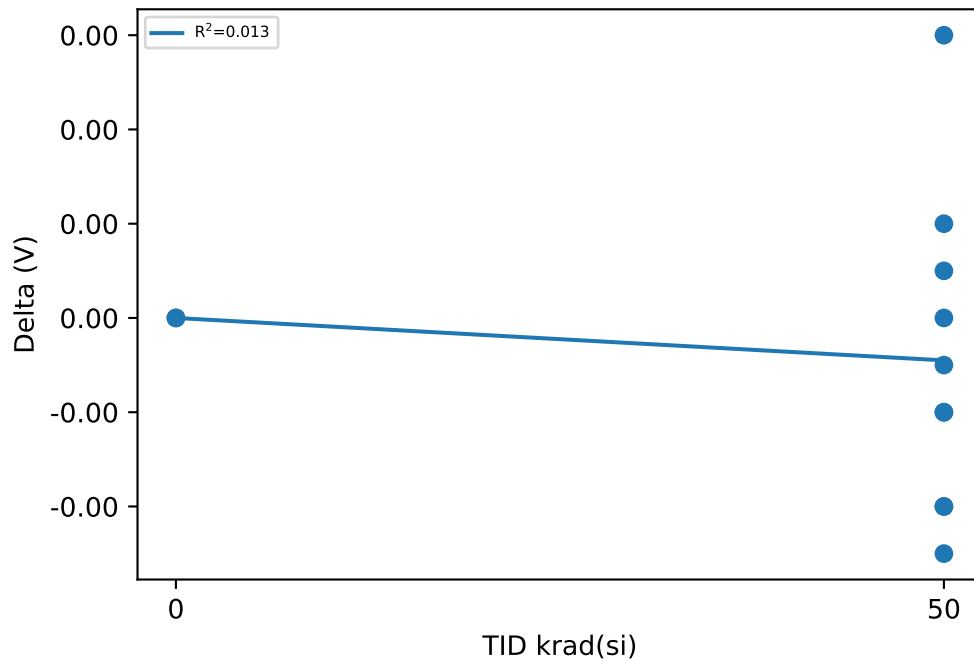
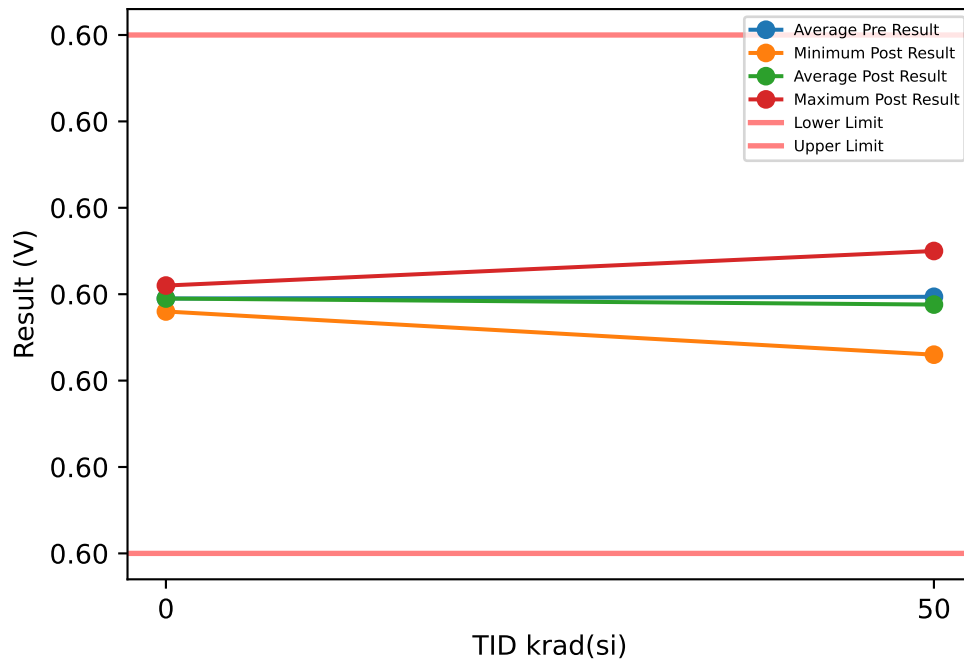
TID vs Post - Pre Exposure Delta



Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0454	0.0501	0.0548	0.0066468	0.0329	0.0407	0.0485	0.011031	-0.0125	-0.0094	-0.0063	0.0043841
50	0.0017	0.05166	0.136	0.042464	-0.0045	0.06416	0.136	0.047415	-0.0843	0.0125	0.1093	0.063809

Device Test: 19.40 VREF_25C(VOLTAGE|VREF//5/5/0/0/5/500kHz//@VREF_25C)



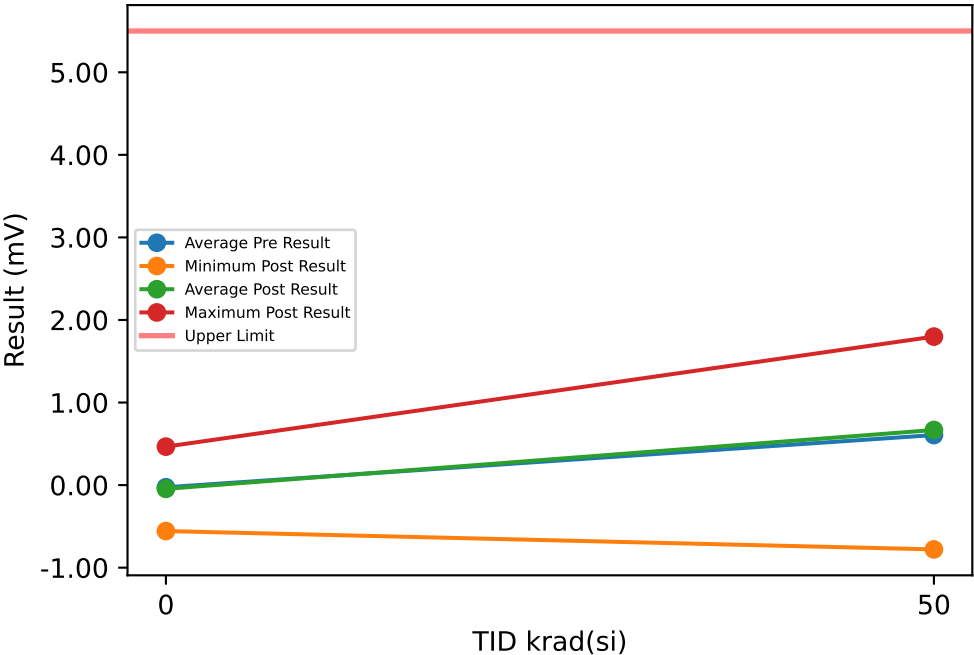
Test Results (Lower Limit = 0.597,
Upper Limit = 0.603 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5998	0.5998	0
2	0	Correlation	0.6001	0.6001	0
4	50	Bias	0.5998	0.5993	-0.0005
6	50	Bias	0.5998	0.5994	-0.0004
7	50	Bias	0.6003	0.6003	0
8	50	Bias	0.5999	0.5997	-0.0002
9	50	Bias	0.5999	0.5997	-0.0002
11	50	Unbias	0.6001	0.6003	0.0002
12	50	Unbias	0.6002	0.6003	0.0001
13	50	Unbias	0.6001	0.6	-0.0001
14	50	Unbias	0.5997	0.5993	-0.0004
15	50	Unbias	0.5999	0.6005	0.0006

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5998	0.59995	0.6001	0.00021213	0.5998	0.59995	0.6001	0.00021213	0	0	0	0
50	0.5997	0.59997	0.6003	0.00019465	0.5993	0.59988	0.6005	0.00045898	-0.0005	-9e-05	0.0006	0.00033149

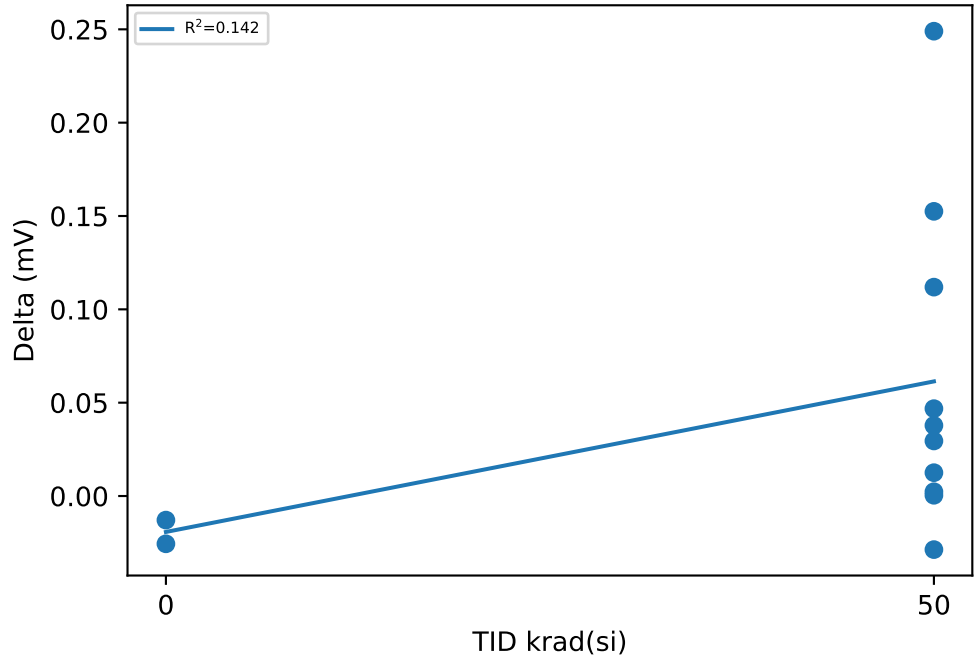
TID vs Result Stats



Test Results (Upper Limit = 5.5 (mV))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.4914	0.4658	-0.0256
2	0	Correlation	-0.5436	-0.5565	-0.0129
4	50	Bias	0.1747	0.2866	0.1119
6	50	Bias	0.6399	0.6112	-0.0287
7	50	Bias	-0.1699	-0.1231	0.0468
8	50	Bias	0.1029	0.2554	0.1525
9	50	Bias	-0.7912	-0.7787	0.0125
11	50	Unbias	1.0711	1.1006	0.0295
12	50	Unbias	1.5495	1.7985	0.249
13	50	Unbias	1.4996	1.5019	0.0023
14	50	Unbias	0.7767	0.7771	0.0004
15	50	Unbias	1.2067	1.2445	0.0378

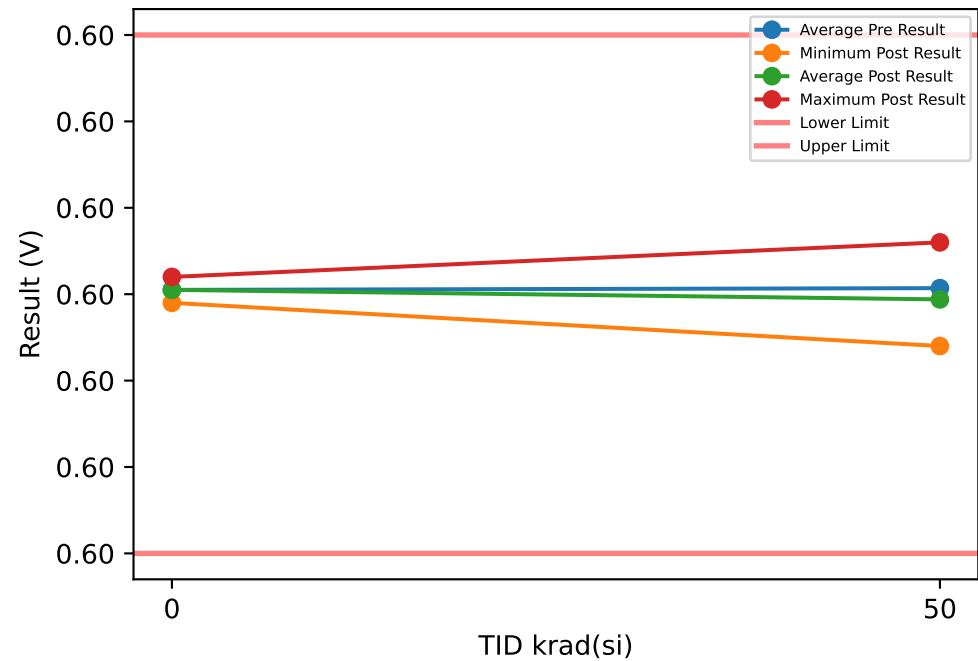
TID vs Post - Pre Exposure Delta



Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.5436	-0.0261	0.4914	0.73186	-0.5565	-0.04535	0.4658	0.72288	-0.0256	-0.01925	-0.0129	0.0089803
50	-0.7912	0.606	1.5495	0.76663	-0.7787	0.6674	1.7985	0.78475	-0.0287	0.0614	0.249	0.085345

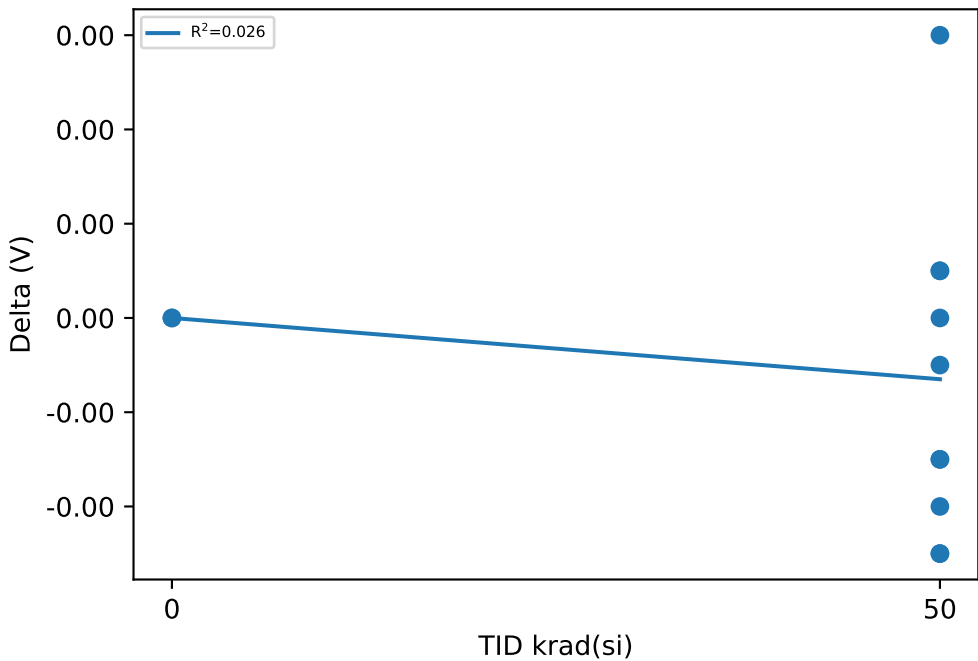
TID vs Result Stats



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5999	0.5999	0
2	0	Correlation	0.6002	0.6002	0
4	50	Bias	0.5999	0.5994	-0.0005
6	50	Bias	0.5999	0.5994	-0.0005
7	50	Bias	0.6004	0.6004	0
8	50	Bias	0.6	0.5997	-0.0003
9	50	Bias	0.6	0.5997	-0.0003
11	50	Unbias	0.6002	0.6003	0.0001
12	50	Unbias	0.6003	0.6004	0.0001
13	50	Unbias	0.6002	0.6001	-0.0001
14	50	Unbias	0.5998	0.5994	-0.0004
15	50	Unbias	0.6	0.6006	0.0006

TID vs Post - Pre Exposure Delta

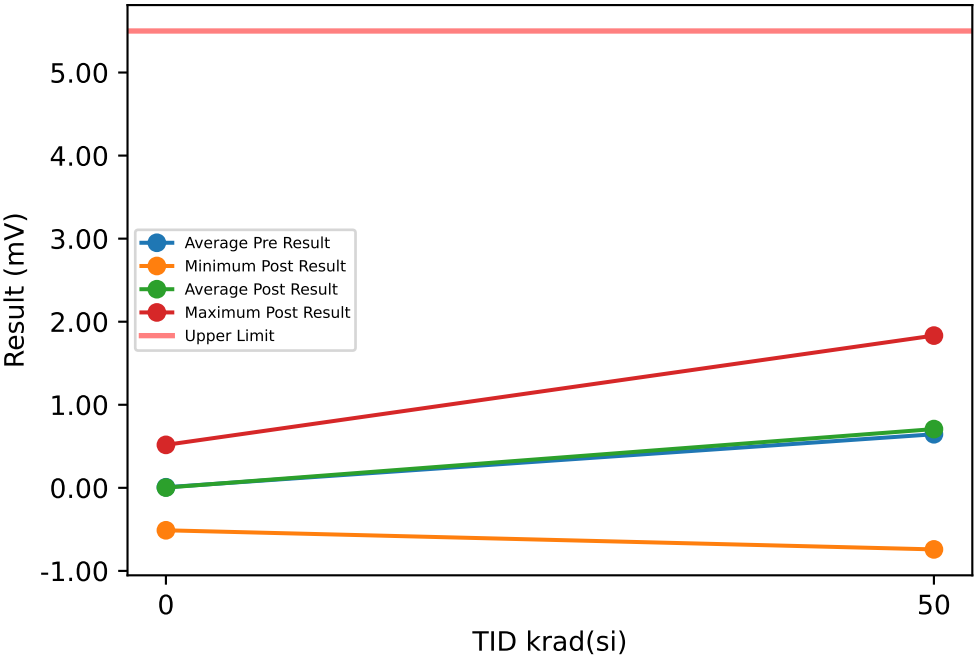


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5999	0.60005	0.6002	0.00021213	0.5999	0.60005	0.6002	0.00021213	0	0	0	0
50	0.5998	0.60007	0.6004	0.00019465	0.5994	0.59994	0.6006	0.00047188	-0.0005	-0.00013	0.0006	0.00034335

Device Test: 19.45 EA_OS(VOLTAGE|OFFSET//12/12/0/0/5/500kHz//@EA_OS)

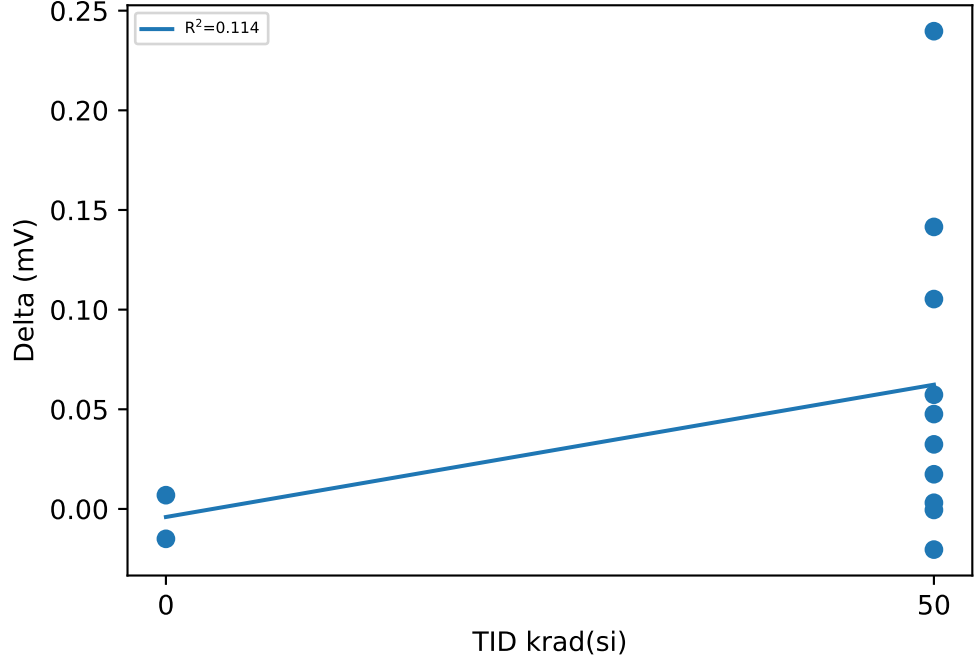
TID vs Result Stats



Test Results (Upper Limit = 5.5 (mV))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5322	0.5172	-0.015
2	0	Correlation	-0.5181	-0.5112	0.0069
4	50	Bias	0.2189	0.3242	0.1053
6	50	Bias	0.6763	0.6559	-0.0204
7	50	Bias	-0.1337	-0.0764	0.0573
8	50	Bias	0.1456	0.2871	0.1415
9	50	Bias	-0.7586	-0.7412	0.0174
11	50	Unbias	1.111	1.1434	0.0324
12	50	Unbias	1.5932	1.8329	0.2397
13	50	Unbias	1.5405	1.54	-0.0005
14	50	Unbias	0.8191	0.8222	0.0031
15	50	Unbias	1.2374	1.285	0.0476

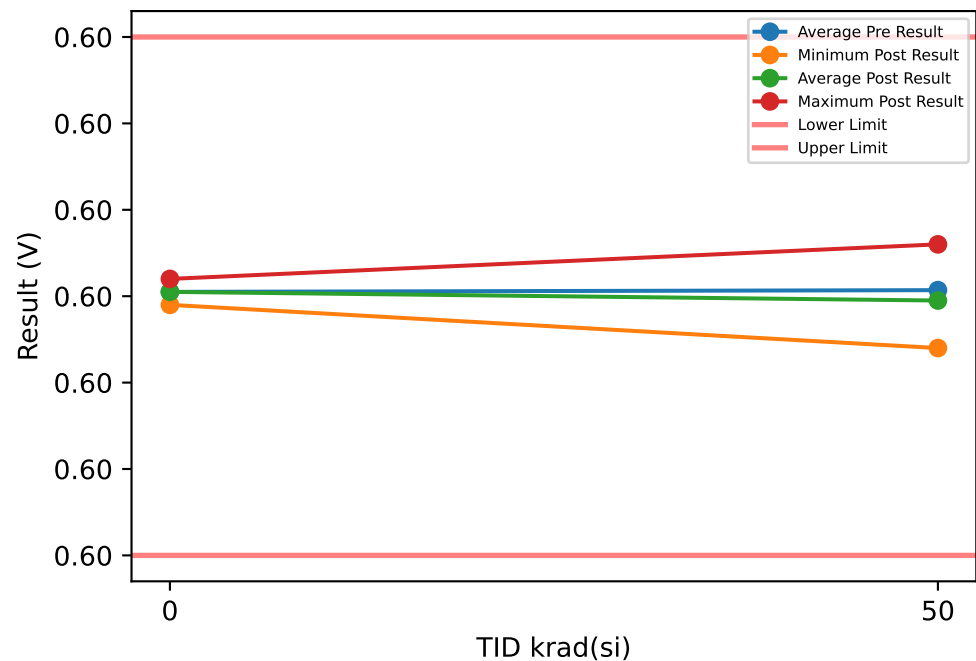
TID vs Post - Pre Exposure Delta



Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.5181	0.00705	0.5322	0.74267	-0.5112	0.003	0.5172	0.72719	-0.015	-0.00405	0.0069	0.015486
50	-0.7586	0.64497	1.5932	0.76796	-0.7412	0.70731	1.8329	0.78428	-0.0204	0.06234	0.2397	0.079604

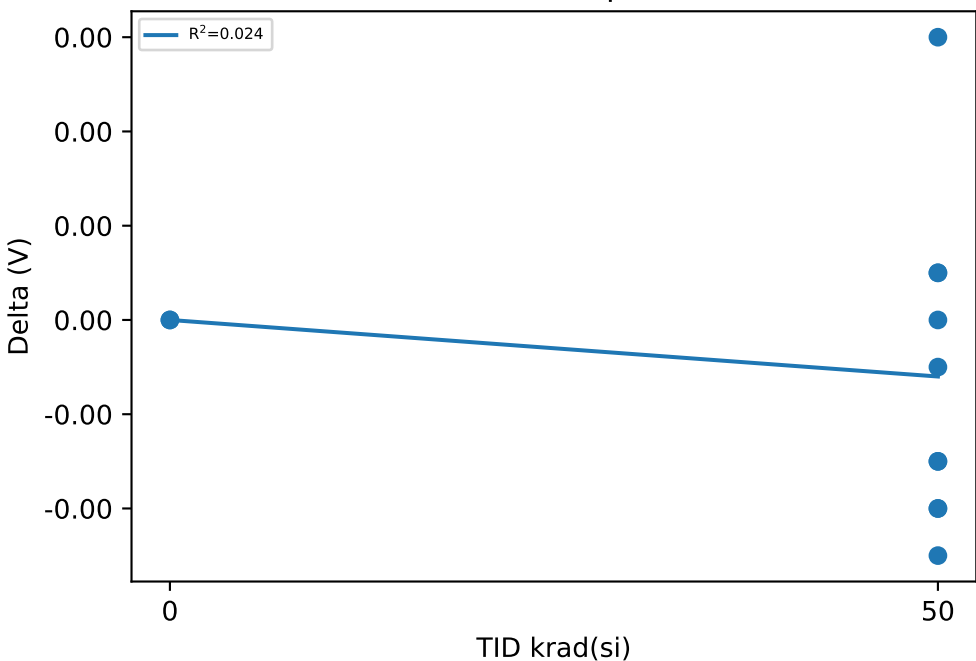
TID vs Result Stats



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5999	0.5999	0
2	0	Correlation	0.6002	0.6002	0
4	50	Bias	0.5999	0.5994	-0.0005
6	50	Bias	0.5999	0.5995	-0.0004
7	50	Bias	0.6004	0.6004	0
8	50	Bias	0.6	0.5997	-0.0003
9	50	Bias	0.6	0.5997	-0.0003
11	50	Unbias	0.6002	0.6003	0.0001
12	50	Unbias	0.6003	0.6004	0.0001
13	50	Unbias	0.6002	0.6001	-0.0001
14	50	Unbias	0.5998	0.5994	-0.0004
15	50	Unbias	0.6	0.6006	0.0006

TID vs Post - Pre Exposure Delta

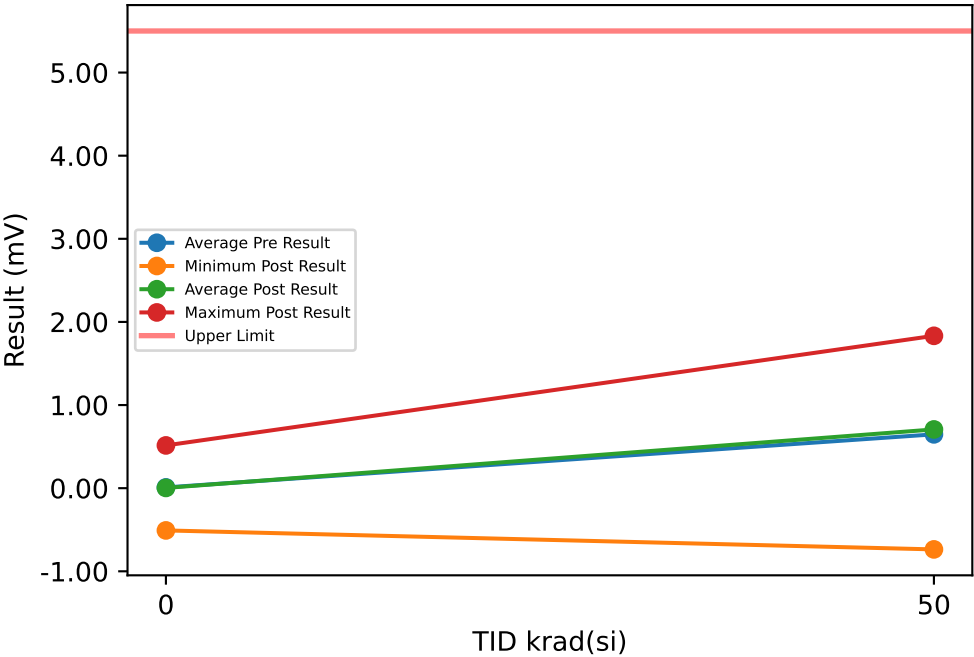


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5999	0.60005	0.6002	0.00021213	0.5999	0.60005	0.6002	0.00021213	0	0	0	0
50	0.5998	0.60007	0.6004	0.00019465	0.5994	0.59995	0.6006	0.00046007	-0.0005	-0.00012	0.0006	0.00033267

Device Test: 19.48 EA_OS(VOLTAGE|OFFSET//14/14/0/0/5/500kHz//@EA_OS)

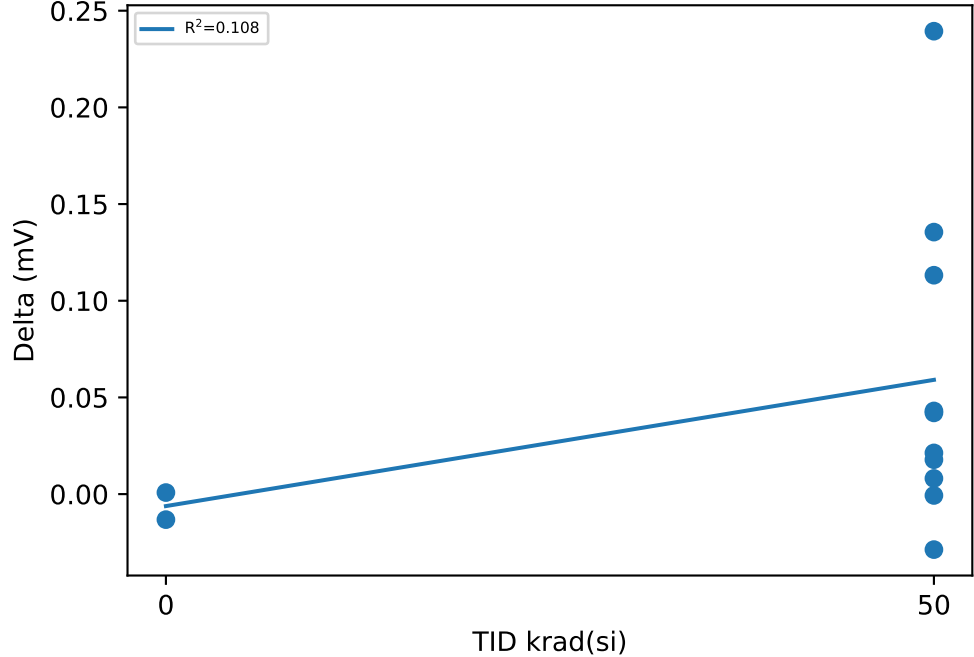
TID vs Result Stats



Test Results (Upper Limit = 5.5 (mV))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5276	0.5144	-0.0132
2	0	Correlation	-0.509	-0.5082	0.0008
4	50	Bias	0.216	0.3292	0.1132
6	50	Bias	0.6846	0.6559	-0.0287
7	50	Bias	-0.1281	-0.0851	0.043
8	50	Bias	0.149	0.2845	0.1355
9	50	Bias	-0.7543	-0.7365	0.0178
11	50	Unbias	1.1086	1.1299	0.0213
12	50	Unbias	1.5935	1.8329	0.2394
13	50	Unbias	1.5412	1.5493	0.0081
14	50	Unbias	0.8225	0.8218	-0.0007
15	50	Unbias	1.2431	1.2851	0.042

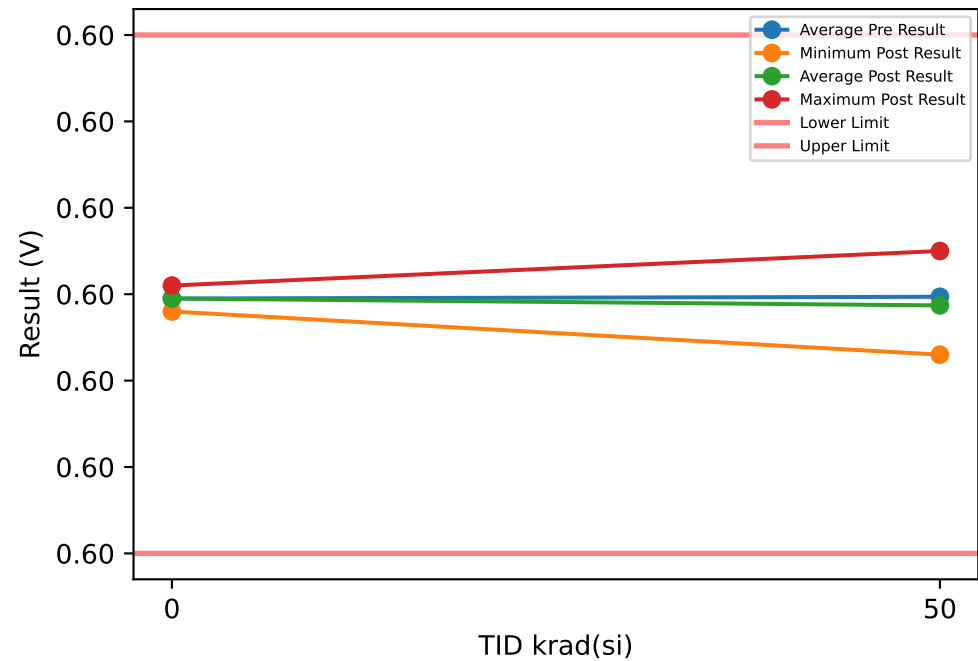
TID vs Post - Pre Exposure Delta



Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.509	0.0093	0.5276	0.73299	-0.5082	0.0031	0.5144	0.72309	-0.0132	-0.0062	0.0008	0.0098995
50	-0.7543	0.64761	1.5935	0.76698	-0.7365	0.7067	1.8329	0.78445	-0.0287	0.05909	0.2394	0.080859

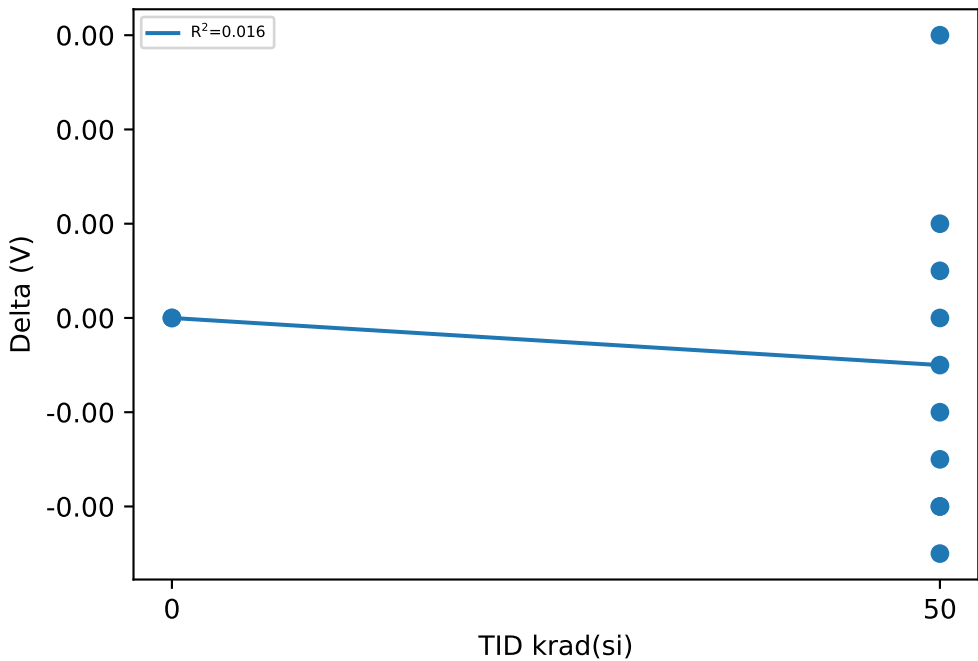
TID vs Result Stats



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5998	0.5998	0
2	0	Correlation	0.6001	0.6001	0
4	50	Bias	0.5998	0.5993	-0.0005
6	50	Bias	0.5998	0.5994	-0.0004
7	50	Bias	0.6003	0.6003	0
8	50	Bias	0.5999	0.5997	-0.0002
9	50	Bias	0.5999	0.5996	-0.0003
11	50	Unbias	0.6001	0.6003	0.0002
12	50	Unbias	0.6002	0.6003	0.0001
13	50	Unbias	0.6001	0.6	-0.0001
14	50	Unbias	0.5997	0.5993	-0.0004
15	50	Unbias	0.5999	0.6005	0.0006

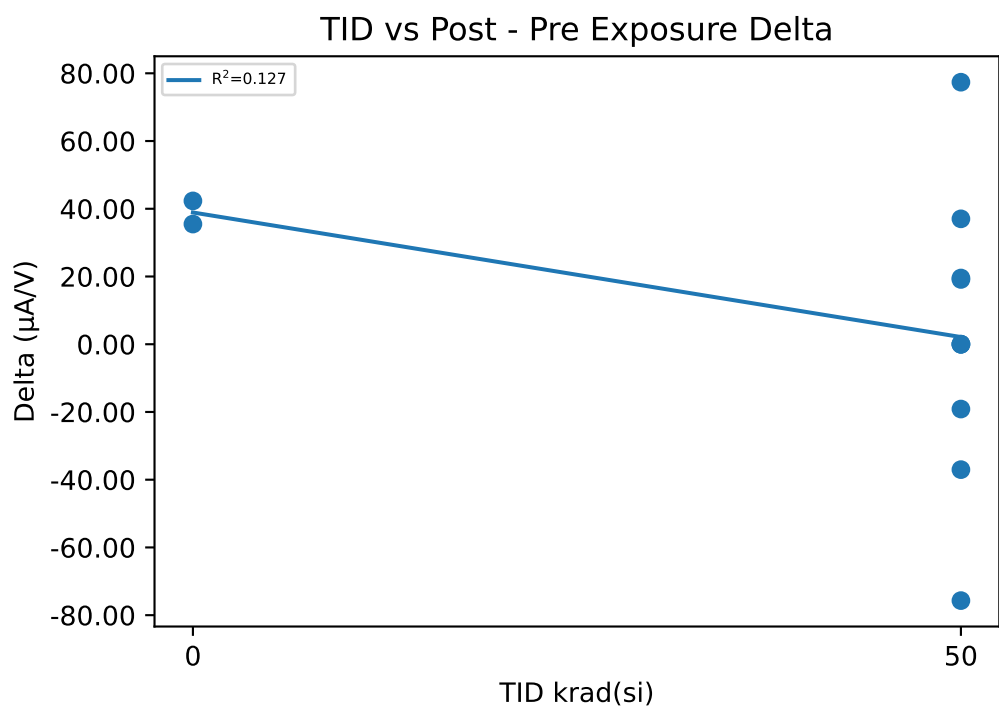
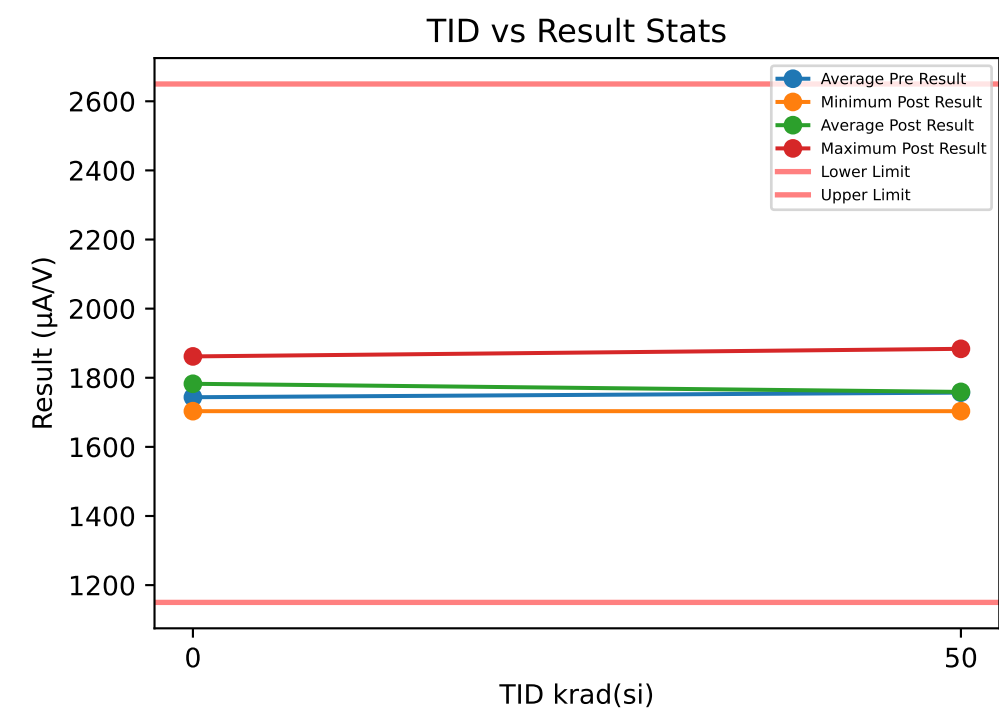
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5998	0.59995	0.6001	0.00021213	0.5998	0.59995	0.6001	0.00021213	0	0	0	0
50	0.5997	0.59997	0.6003	0.00019465	0.5993	0.59987	0.6005	0.0004644	-0.0005	-0.0001	0.0006	0.00033665

Device Test: 19.5 EA_GM(LEVEL|TRANSCONDUCTANCE//5/5/0/0/5/500kHz//@EA_GM)



Test Results (Lower Limit = 1150.0, Upper Limit = 2650.0 (µA/V))

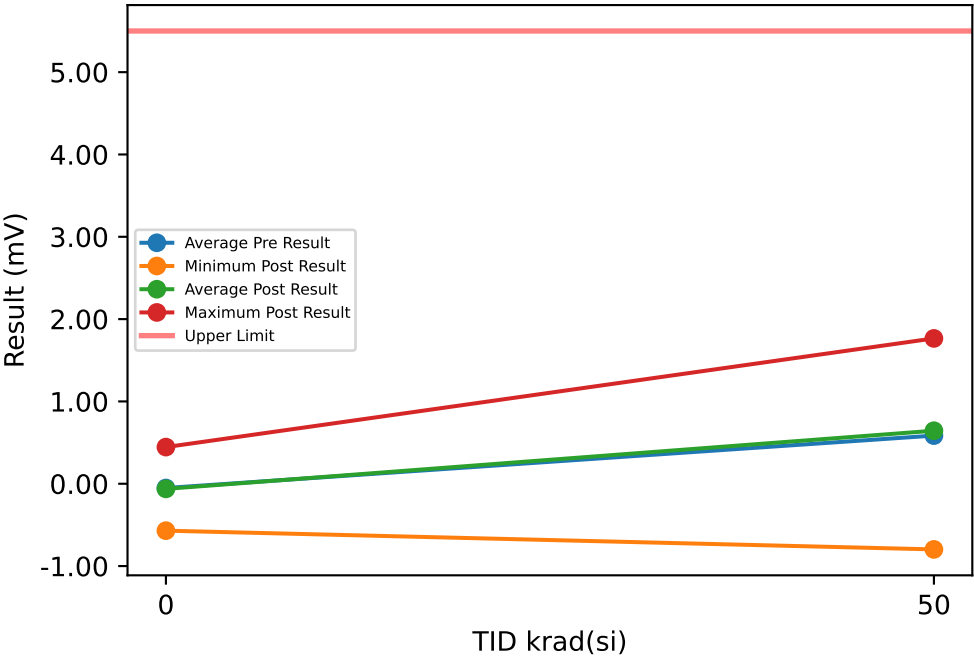
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1819.5	1861.8	42.32
2	0	Correlation	1667.8	1703.3	35.483
4	50	Bias	1759.5	1740.3	-19.137
6	50	Bias	1779	1779	0
7	50	Bias	1703.3	1703.3	0.0087
8	50	Bias	1759.5	1779	19.553
9	50	Bias	1779	1703.3	-75.697
11	50	Unbias	1740.4	1759.5	19.128
12	50	Unbias	1740.4	1703.3	-37.026
13	50	Unbias	1721.6	1799	77.371
14	50	Unbias	1703.3	1740.4	37.026
15	50	Unbias	1883.7	1883.7	0.0106

Test Statistics (µA/V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1667.8	1743.7	1819.5	107.2	1703.3	1782.6	1861.8	112.04	35.483	38.901	42.32	4.834
50	1703.3	1757	1883.7	52.275	1703.3	1759.1	1883.7	55.72	-75.697	2.1237	77.371	41.536

Device Test: 19.51 EA_OS(VOLTAGE|OFFSET//4.5/4.5/0/0/4.5/1MHz//@EA_OS)

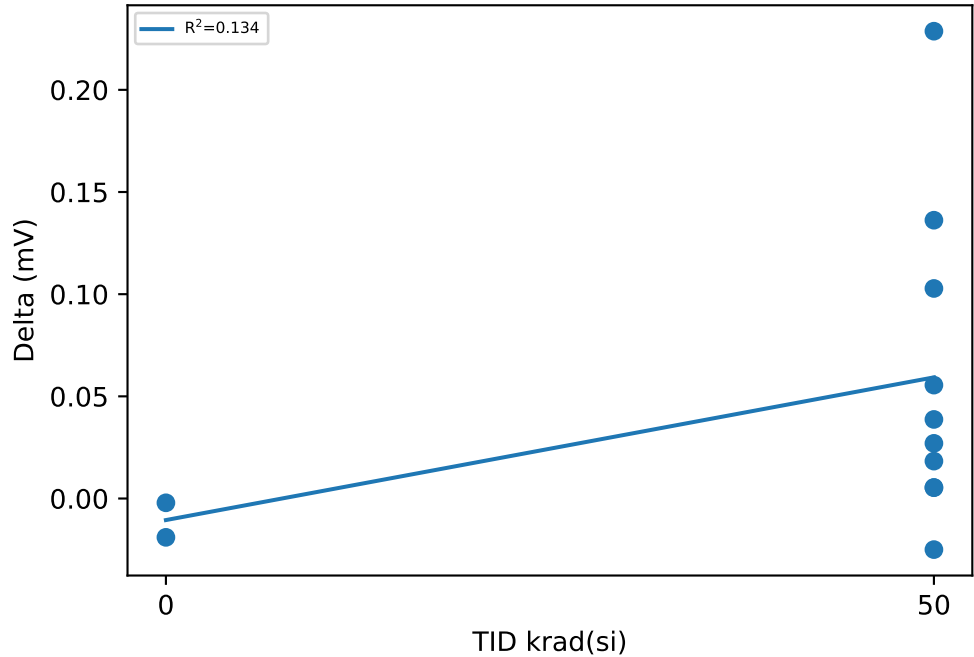
TID vs Result Stats



Test Results (Upper Limit = 5.5 (mV))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.4644	0.4454	-0.019
2	0	Correlation	-0.5678	-0.5699	-0.0021
4	50	Bias	0.1608	0.2636	0.1028
6	50	Bias	0.6117	0.5867	-0.025
7	50	Bias	-0.1994	-0.1439	0.0555
8	50	Bias	0.0863	0.2225	0.1362
9	50	Bias	-0.8158	-0.7975	0.0183
11	50	Unbias	1.0471	1.0741	0.027
12	50	Unbias	1.5369	1.7656	0.2287
13	50	Unbias	1.4799	1.4852	0.0053
14	50	Unbias	0.7585	0.7639	0.0054
15	50	Unbias	1.1833	1.222	0.0387

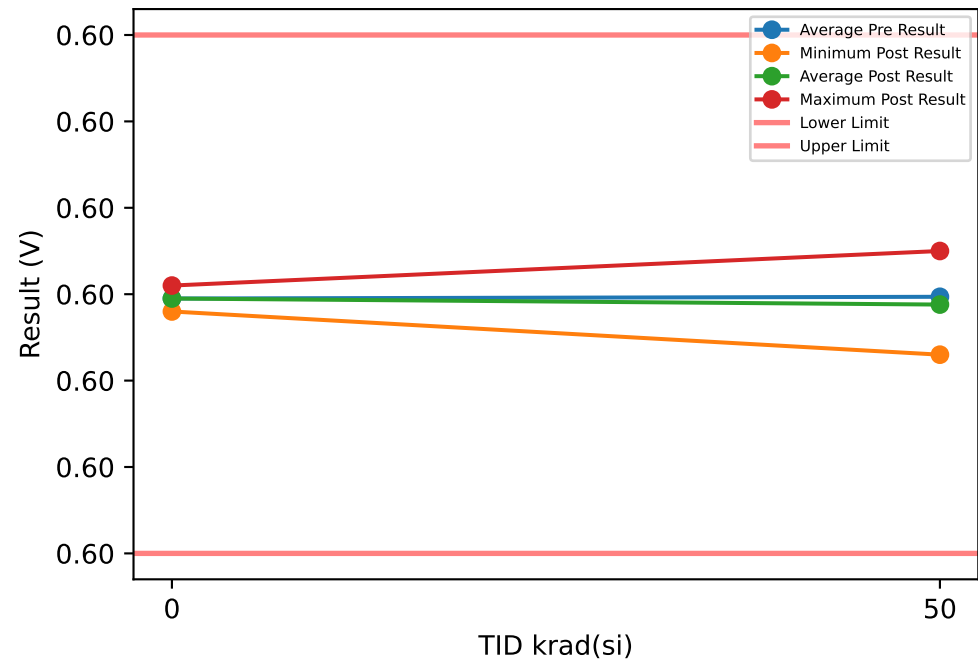
TID vs Post - Pre Exposure Delta



Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.5678	-0.0517	0.4644	0.72988	-0.5699	-0.06225	0.4454	0.71793	-0.019	-0.01055	-0.0021	0.01195
50	-0.8158	0.58493	1.5369	0.76851	-0.7975	0.64422	1.7656	0.7834	-0.025	0.05929	0.2287	0.076444

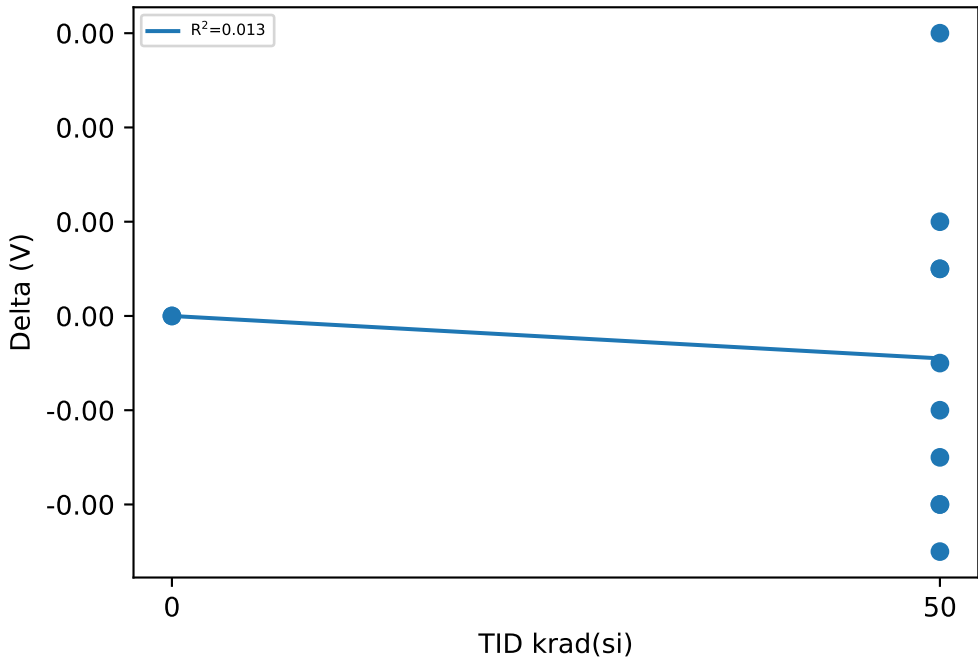
TID vs Result Stats



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5998	0.5998	0
2	0	Correlation	0.6001	0.6001	0
4	50	Bias	0.5998	0.5993	-0.0005
6	50	Bias	0.5998	0.5994	-0.0004
7	50	Bias	0.6003	0.6004	0.0001
8	50	Bias	0.5999	0.5997	-0.0002
9	50	Bias	0.5999	0.5996	-0.0003
11	50	Unbias	0.6001	0.6003	0.0002
12	50	Unbias	0.6002	0.6003	0.0001
13	50	Unbias	0.6001	0.6	-0.0001
14	50	Unbias	0.5997	0.5993	-0.0004
15	50	Unbias	0.5999	0.6005	0.0006

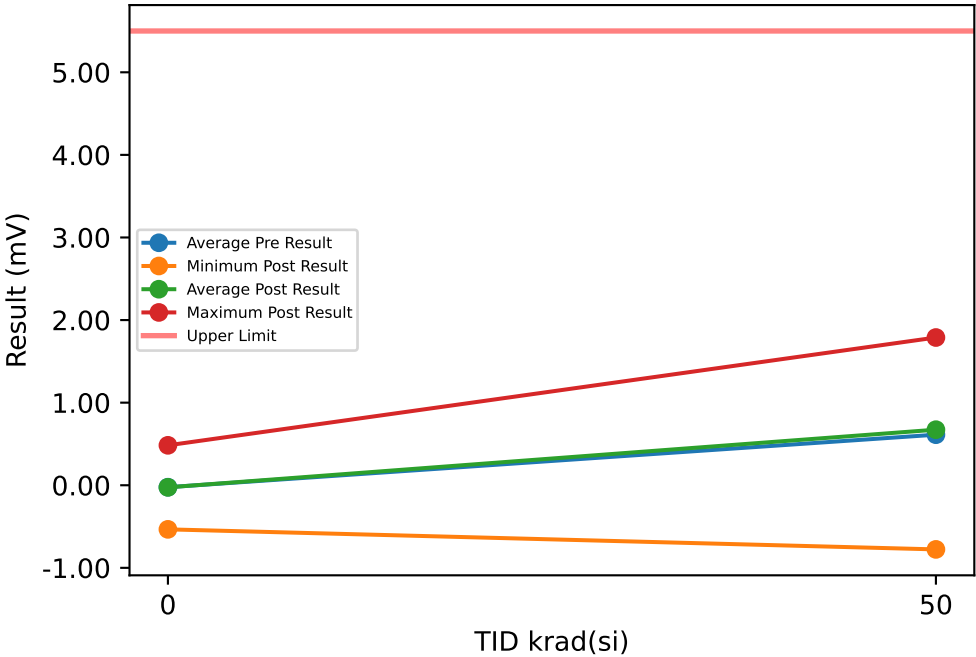
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5998	0.59995	0.6001	0.00021213	0.5998	0.59995	0.6001	0.00021213	0	0	0	0
50	0.5997	0.59997	0.6003	0.00019465	0.5993	0.59988	0.6005	0.00047563	-0.0005	-9e-05	0.0006	0.0003414

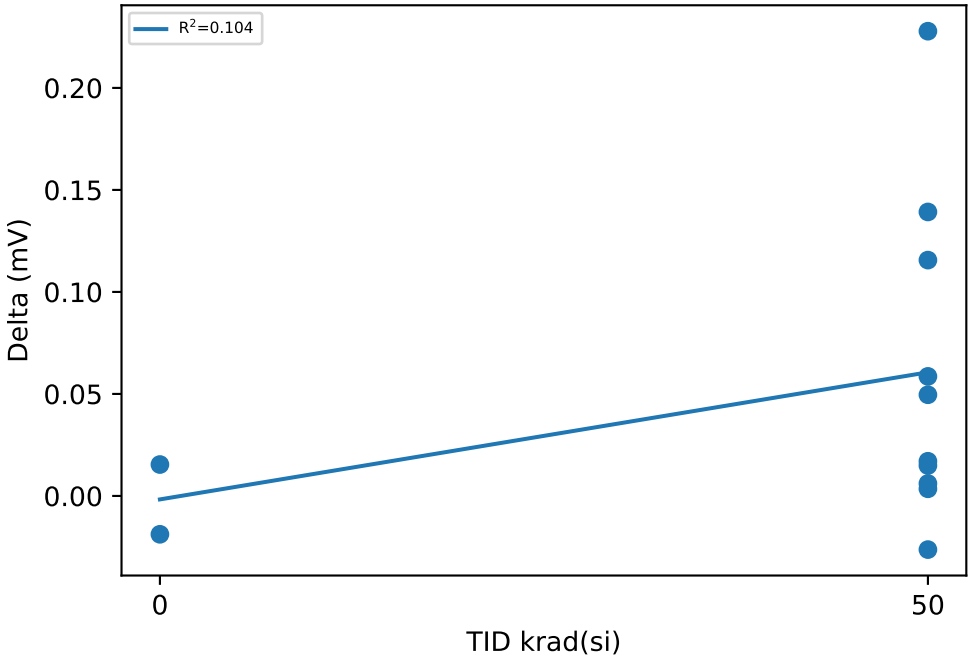
TID vs Result Stats



Test Results (Upper Limit = 5.5 (mV))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5023	0.4835	-0.0188
2	0	Correlation	-0.5494	-0.534	0.0154
4	50	Bias	0.1788	0.2944	0.1156
6	50	Bias	0.6445	0.6182	-0.0263
7	50	Bias	-0.1704	-0.1118	0.0586
8	50	Bias	0.1143	0.2535	0.1392
9	50	Bias	-0.7916	-0.7767	0.0149
11	50	Unbias	1.0833	1.1003	0.017
12	50	Unbias	1.5609	1.7887	0.2278
13	50	Unbias	1.5037	1.5098	0.0061
14	50	Unbias	0.7933	0.7968	0.0035
15	50	Unbias	1.2043	1.2539	0.0496

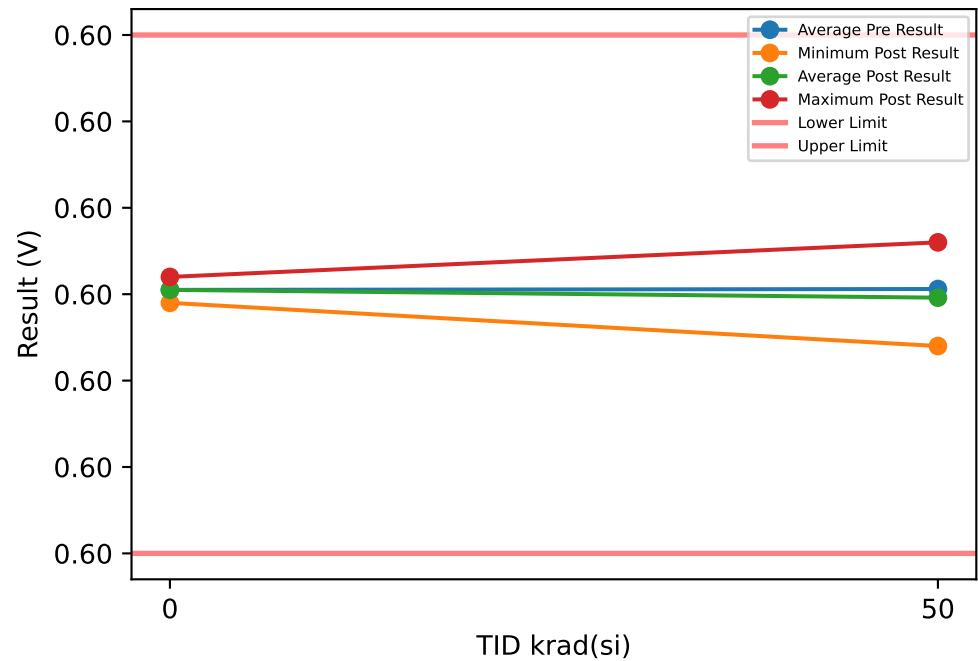
TID vs Post - Pre Exposure Delta



Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.5494	-0.02355	0.5023	0.74366	-0.534	-0.02525	0.4835	0.71948	-0.0188	-0.0017	0.0154	0.024183
50	-0.7916	0.61211	1.5609	0.76884	-0.7767	0.67271	1.7887	0.78317	-0.0263	0.0606	0.2278	0.078213

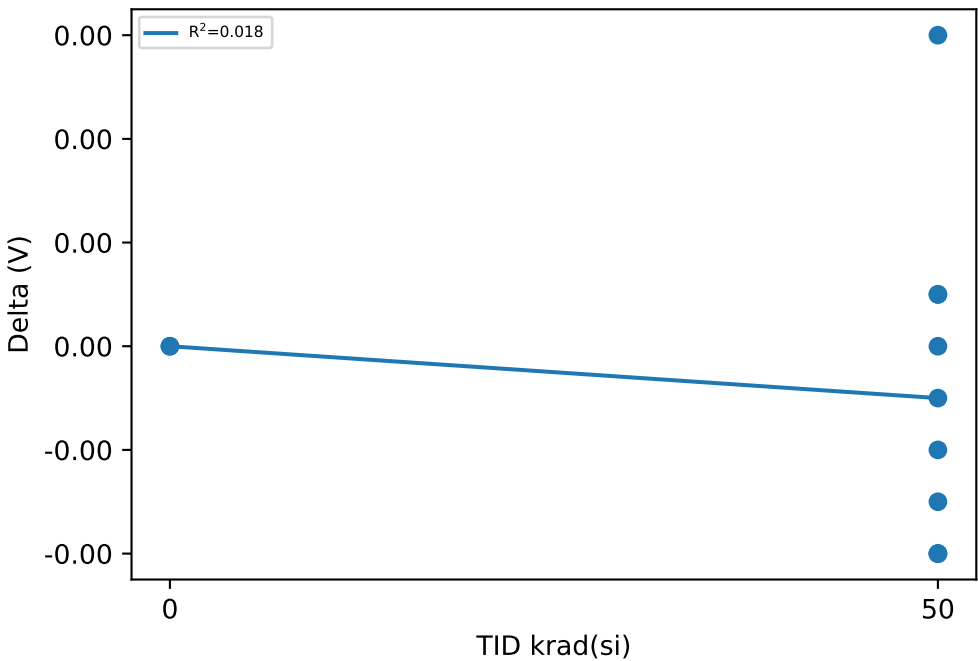
TID vs Result Stats



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5999	0.5999	0
2	0	Correlation	0.6002	0.6002	0
4	50	Bias	0.5998	0.5994	-0.0004
6	50	Bias	0.5999	0.5995	-0.0004
7	50	Bias	0.6004	0.6004	0
8	50	Bias	0.6	0.5998	-0.0002
9	50	Bias	0.6	0.5997	-0.0003
11	50	Unbias	0.6002	0.6003	0.0001
12	50	Unbias	0.6003	0.6004	0.0001
13	50	Unbias	0.6002	0.6001	-0.0001
14	50	Unbias	0.5998	0.5994	-0.0004
15	50	Unbias	0.6	0.6006	0.0006

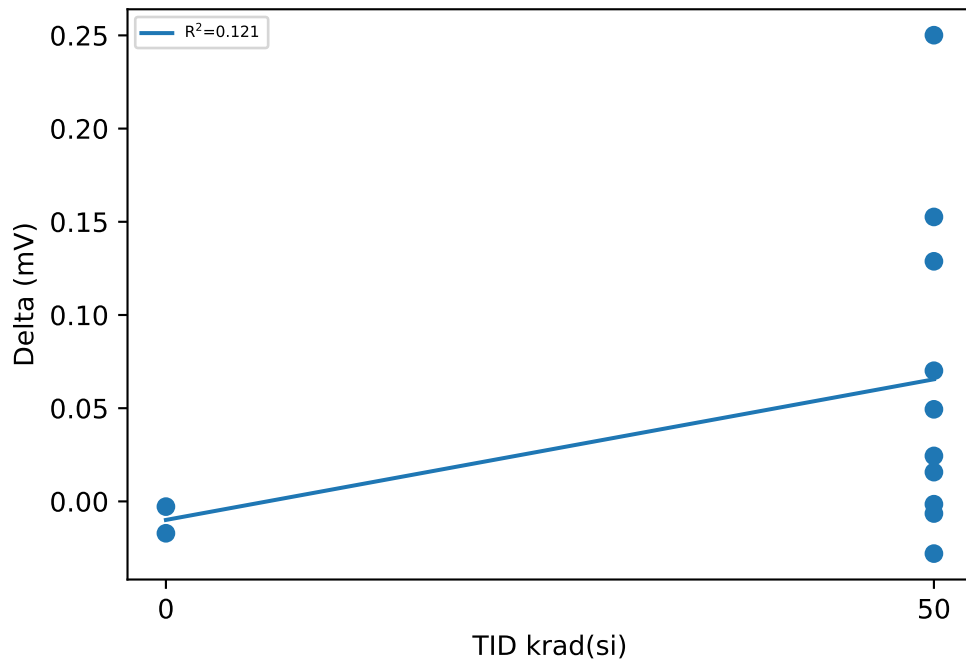
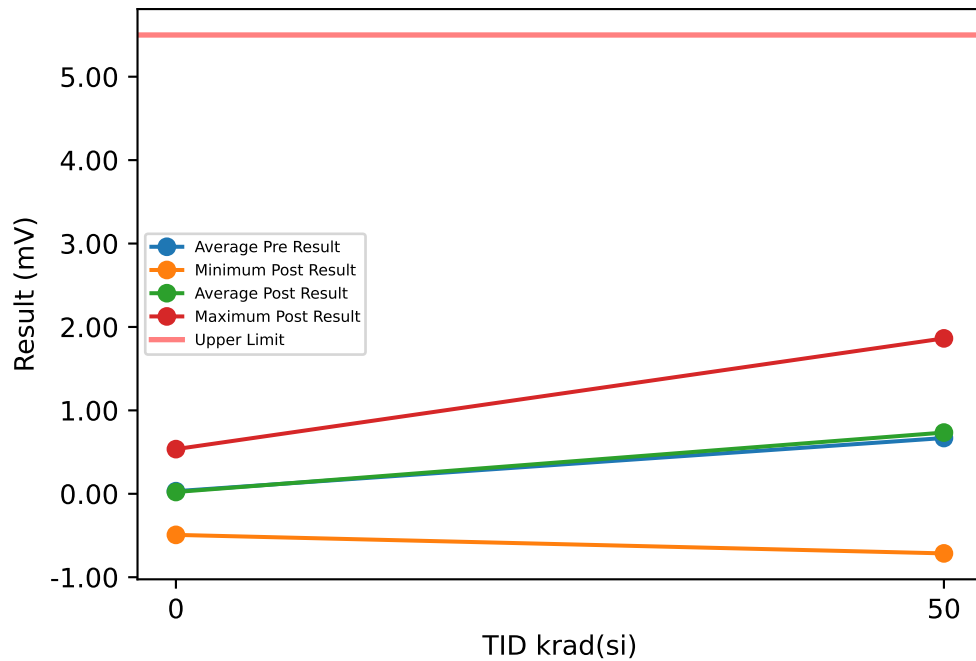
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5999	0.60005	0.6002	0.00021213	0.5999	0.60005	0.6002	0.00021213	0	0	0	0
50	0.5998	0.60006	0.6004	0.00020656	0.5994	0.59996	0.6006	0.00045509	-0.0004	-0.0001	0.0006	0.00031623

Device Test: 19.57 EA_OS(VOLTAGE|OFFSET//12/12/0/0/5/1MHz//@EA_OS)



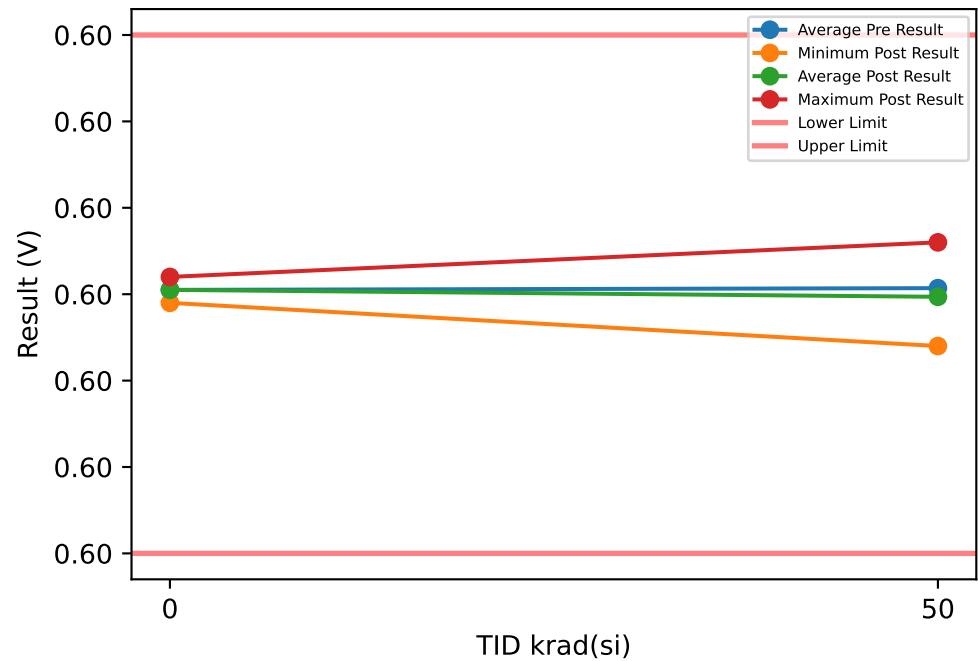
Test Results (Upper Limit = 5.5 (mV))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5525	0.5354	-0.0171
2	0	Correlation	-0.4897	-0.4925	-0.0028
4	50	Bias	0.2265	0.3553	0.1288
6	50	Bias	0.7092	0.6812	-0.028
7	50	Bias	-0.117	-0.0469	0.0701
8	50	Bias	0.1625	0.3151	0.1526
9	50	Bias	-0.7302	-0.7145	0.0157
11	50	Unbias	1.1403	1.1647	0.0244
12	50	Unbias	1.6129	1.863	0.2501
13	50	Unbias	1.5696	1.5681	-0.0015
14	50	Unbias	0.8497	0.8432	-0.0065
15	50	Unbias	1.2631	1.3125	0.0494

Test Statistics (mV)

krad(Si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.4897	0.0314	0.5525	0.73695	-0.4925	0.02145	0.5354	0.72684	-0.0171	-0.00995	-0.0028	0.010112
50	-0.7302	0.66866	1.6129	0.77023	-0.7145	0.73417	1.863	0.78401	-0.028	0.06551	0.2501	0.087264

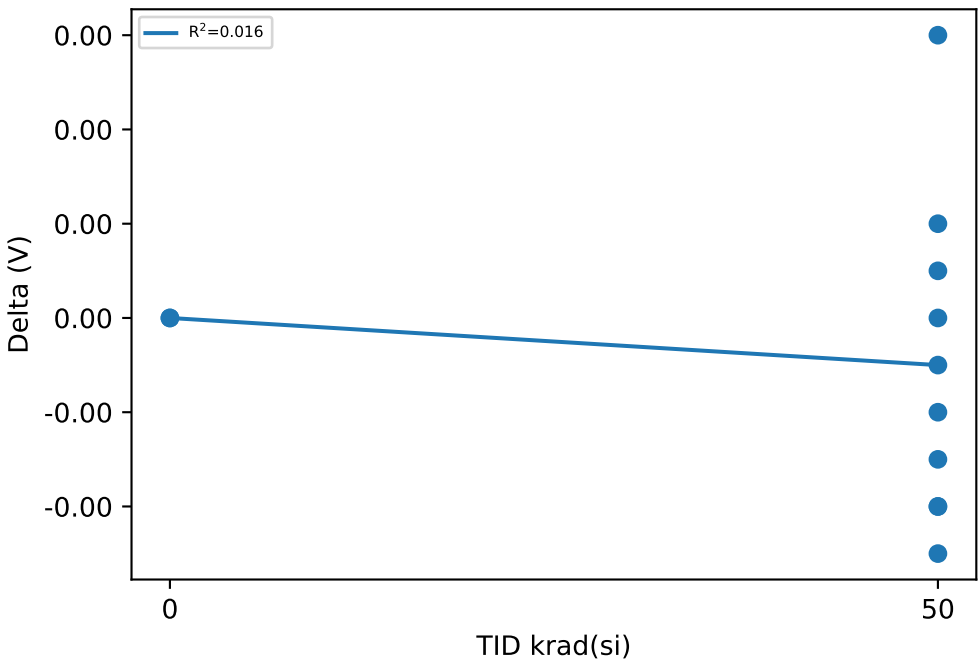
TID vs Result Stats



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5999	0.5999	0
2	0	Correlation	0.6002	0.6002	0
4	50	Bias	0.5999	0.5994	-0.0005
6	50	Bias	0.5999	0.5995	-0.0004
7	50	Bias	0.6004	0.6004	0
8	50	Bias	0.6	0.5998	-0.0002
9	50	Bias	0.6	0.5997	-0.0003
11	50	Unbias	0.6002	0.6004	0.0002
12	50	Unbias	0.6003	0.6004	0.0001
13	50	Unbias	0.6002	0.6001	-0.0001
14	50	Unbias	0.5998	0.5994	-0.0004
15	50	Unbias	0.6	0.6006	0.0006

TID vs Post - Pre Exposure Delta

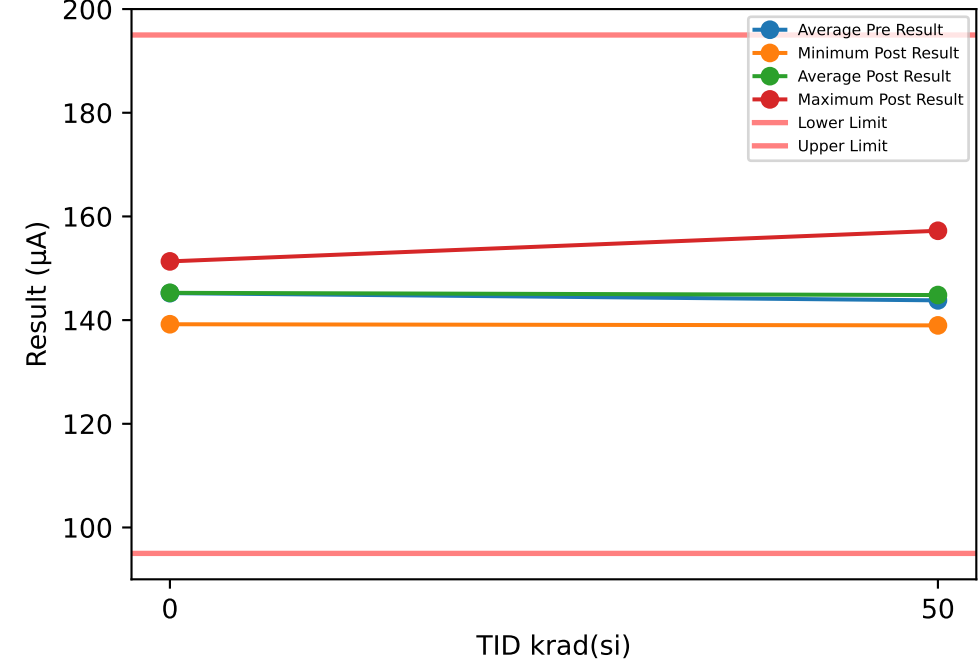


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5999	0.60005	0.6002	0.00021213	0.5999	0.60005	0.6002	0.00021213	0	0	0	0
50	0.5998	0.60007	0.6004	0.00019465	0.5994	0.59997	0.6006	0.0004644	-0.0005	-0.0001	0.0006	0.00033665

Device Test: 19.6 EA_I_SOURCE(CURRENT|EA_SOURCE//5/5/0/0/5/500kHz//@EA_I_SOURCE)

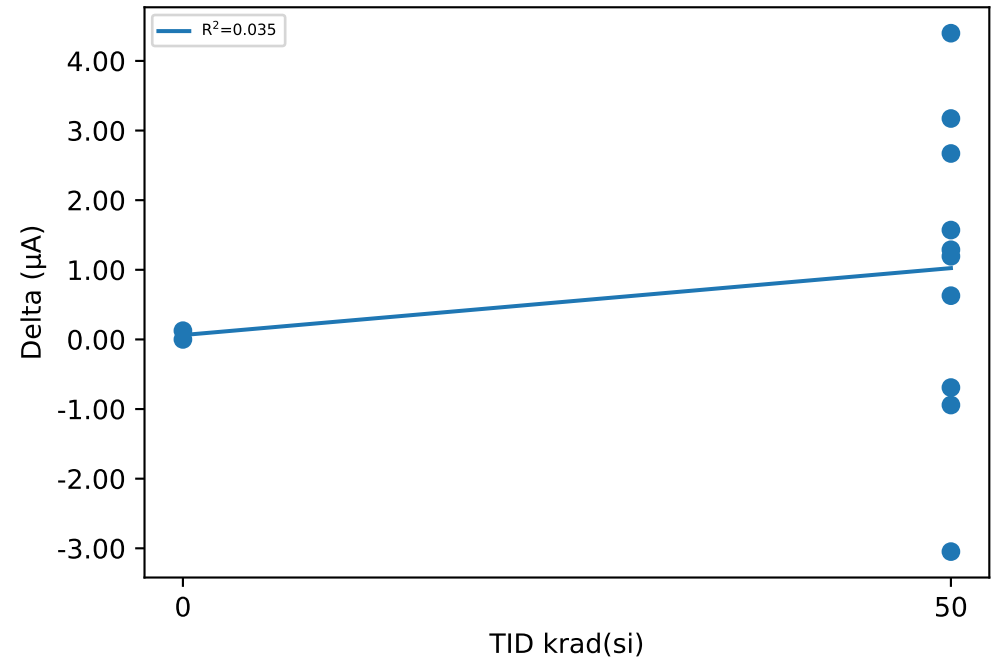
TID vs Result Stats



Test Results (Lower Limit = 95.0, Upper Limit = 195.0 (µA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	151.33	151.33	0
2	0	Correlation	139.08	139.2	0.1256
4	50	Bias	141.46	142.66	1.1937
6	50	Bias	149.79	146.74	-3.0472
7	50	Bias	138.35	138.98	0.6283
8	50	Bias	143.1	145.77	2.6703
9	50	Bias	142.66	141.72	-0.9424
11	50	Unbias	144.23	145.8	1.5707
12	50	Unbias	142.75	142.06	-0.6912
13	50	Unbias	144.98	148.16	3.1729
14	50	Unbias	137.95	139.23	1.288
15	50	Unbias	152.84	157.24	4.3981

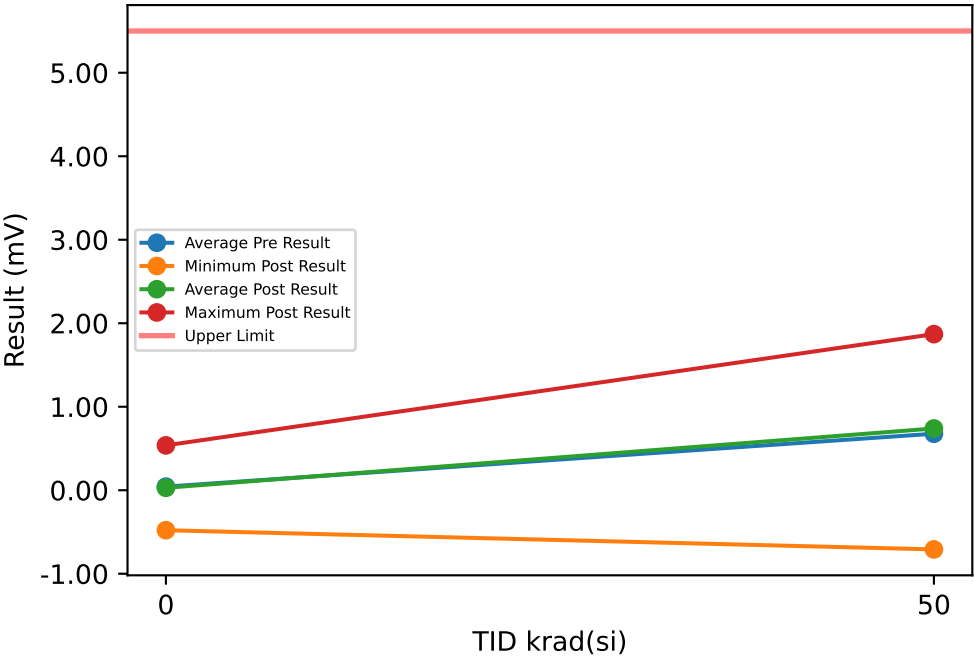
TID vs Post - Pre Exposure Delta



Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	139.08	145.2	151.33	8.6633	139.2	145.27	151.33	8.5744	0	0.0628	0.1256	0.088813
50	137.95	143.81	152.84	4.6114	138.98	144.84	157.24	5.3541	-3.0472	1.0241	4.3981	2.1769

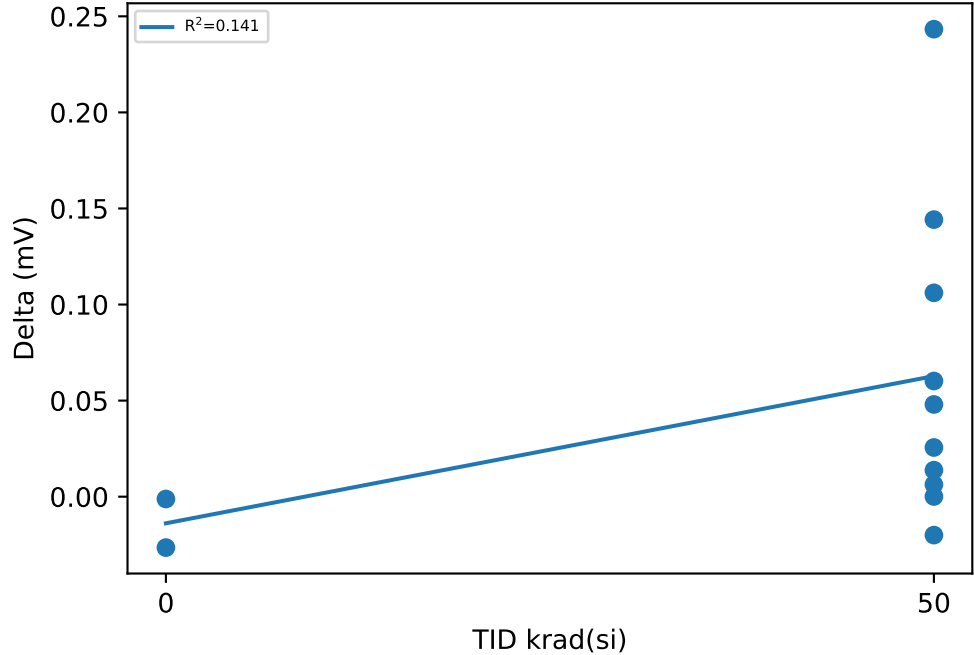
TID vs Result Stats



Test Results (Upper Limit = 5.5 (mV))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5638	0.5373	-0.0265
2	0	Correlation	-0.4776	-0.4788	-0.0012
4	50	Bias	0.2499	0.356	0.1061
6	50	Bias	0.7077	0.6877	-0.02
7	50	Bias	-0.1031	-0.0429	0.0602
8	50	Bias	0.1742	0.3184	0.1442
9	50	Bias	-0.7223	-0.7085	0.0138
11	50	Unbias	1.1387	1.1643	0.0256
12	50	Unbias	1.6264	1.8697	0.2433
13	50	Unbias	1.5754	1.5817	0.0063
14	50	Unbias	0.85	0.8501	0.0001
15	50	Unbias	1.2718	1.3198	0.048

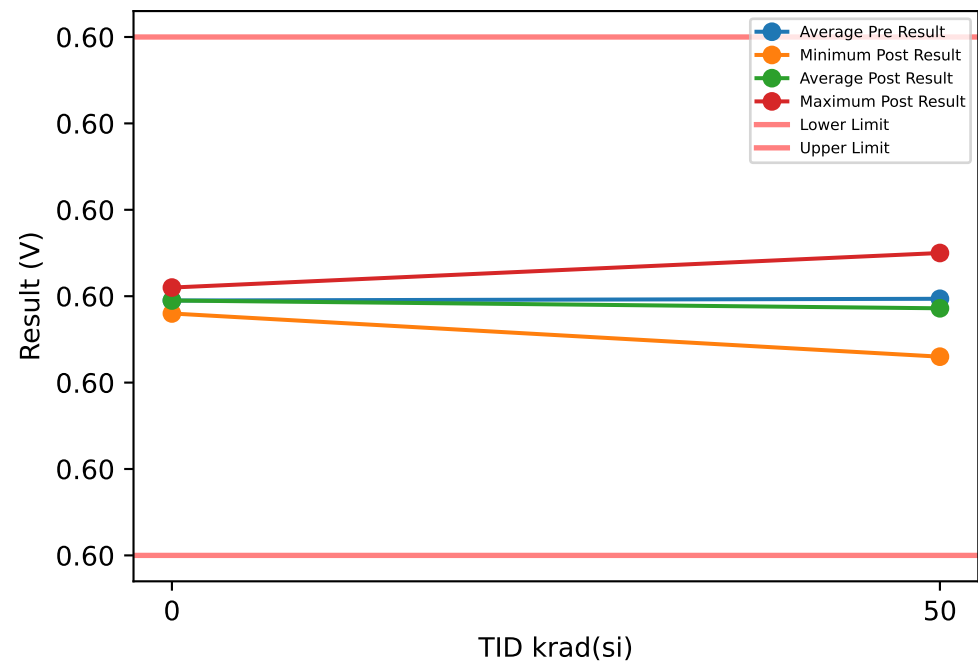
TID vs Post - Pre Exposure Delta



Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.4776	0.0431	0.5638	0.73638	-0.4788	0.02925	0.5373	0.71849	-0.0265	-0.01385	-0.0012	0.01789
50	-0.7223	0.67687	1.6264	0.76798	-0.7085	0.73963	1.8697	0.78542	-0.02	0.06276	0.2433	0.081015

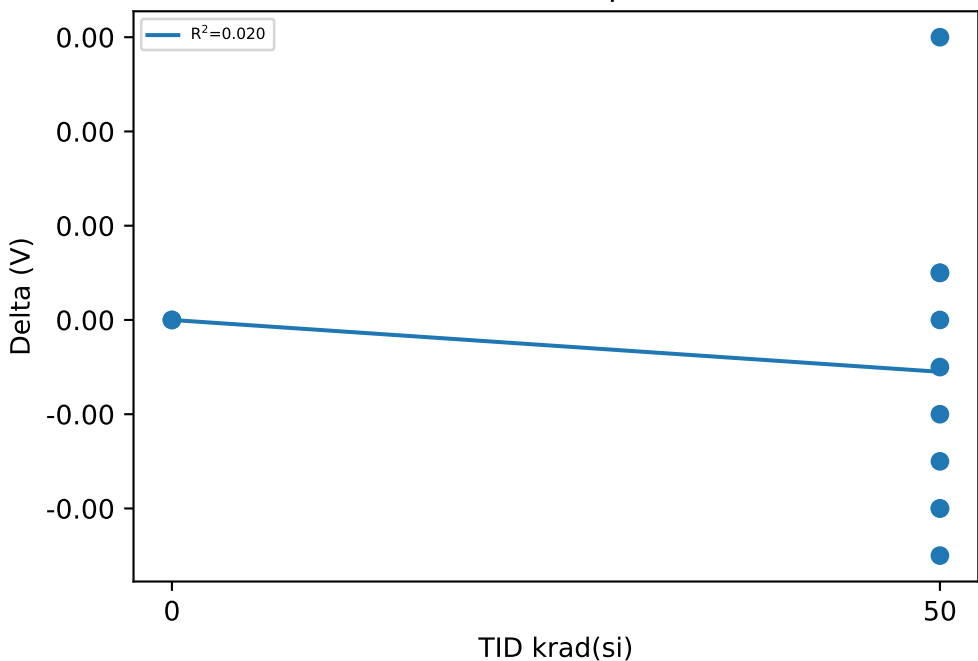
TID vs Result Stats



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5998	0.5998	0
2	0	Correlation	0.6001	0.6001	0
4	50	Bias	0.5998	0.5993	-0.0005
6	50	Bias	0.5998	0.5994	-0.0004
7	50	Bias	0.6003	0.6003	0
8	50	Bias	0.5999	0.5997	-0.0002
9	50	Bias	0.5999	0.5996	-0.0003
11	50	Unbias	0.6001	0.6002	0.0001
12	50	Unbias	0.6002	0.6003	0.0001
13	50	Unbias	0.6001	0.6	-0.0001
14	50	Unbias	0.5997	0.5993	-0.0004
15	50	Unbias	0.5999	0.6005	0.0006

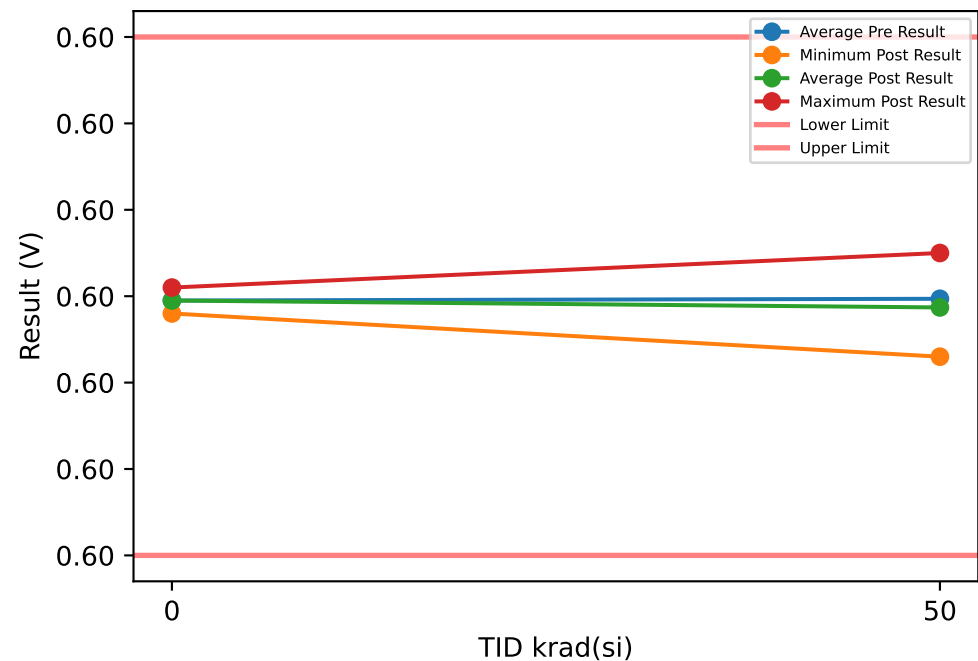
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5998	0.59995	0.6001	0.00021213	0.5998	0.59995	0.6001	0.00021213	0	0	0	0
50	0.5997	0.59997	0.6003	0.00019465	0.5993	0.59986	0.6005	0.00045509	-0.0005	-0.00011	0.0006	0.00032813

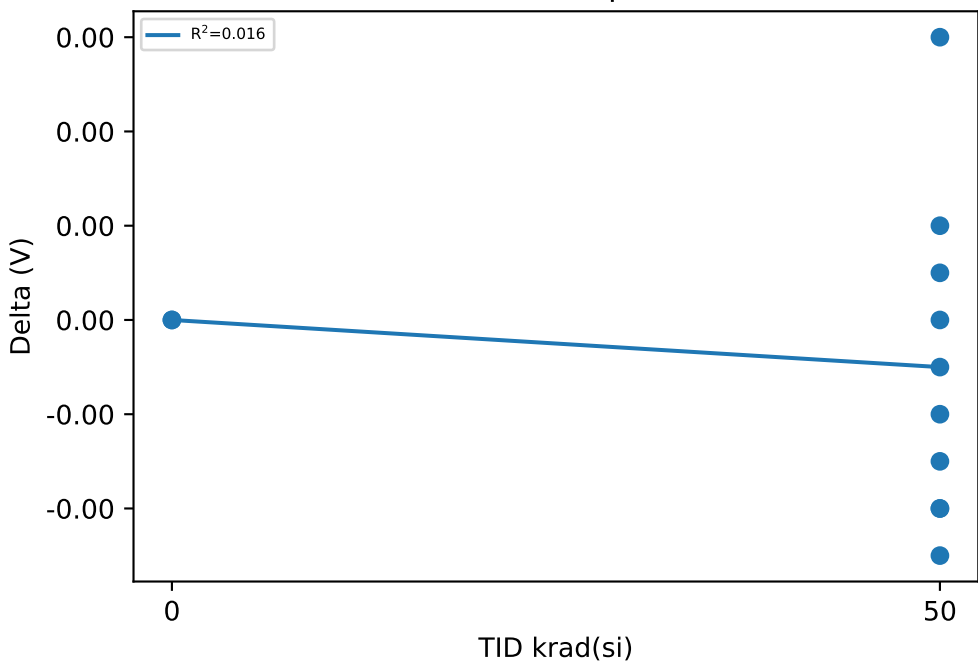
TID vs Result Stats



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5998	0.5998	0
2	0	Correlation	0.6001	0.6001	0
4	50	Bias	0.5998	0.5993	-0.0005
6	50	Bias	0.5998	0.5994	-0.0004
7	50	Bias	0.6003	0.6003	0
8	50	Bias	0.5999	0.5997	-0.0002
9	50	Bias	0.5999	0.5996	-0.0003
11	50	Unbias	0.6001	0.6003	0.0002
12	50	Unbias	0.6002	0.6003	0.0001
13	50	Unbias	0.6001	0.6	-0.0001
14	50	Unbias	0.5997	0.5993	-0.0004
15	50	Unbias	0.5999	0.6005	0.0006

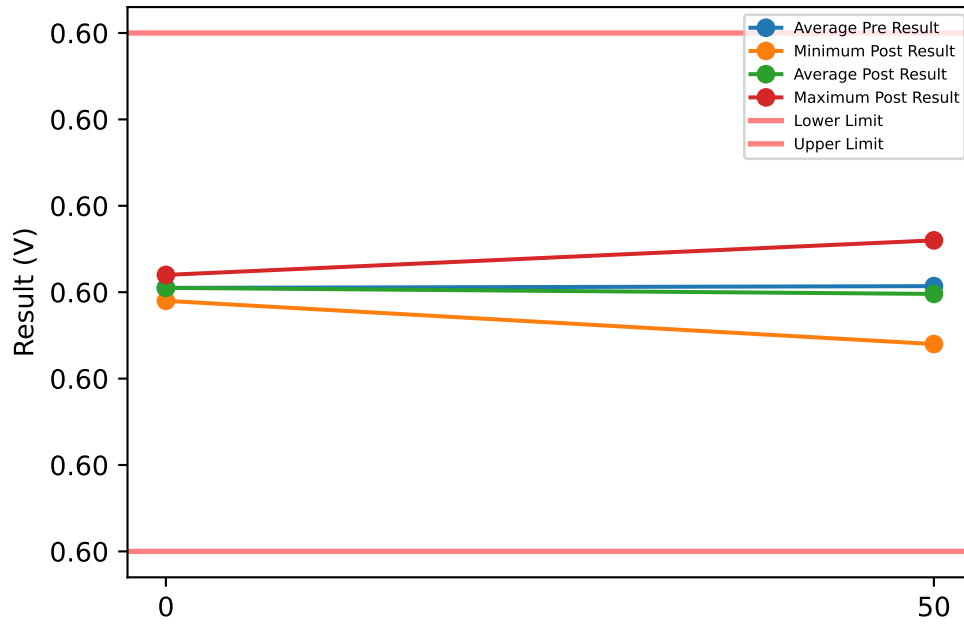
TID vs Post - Pre Exposure Delta



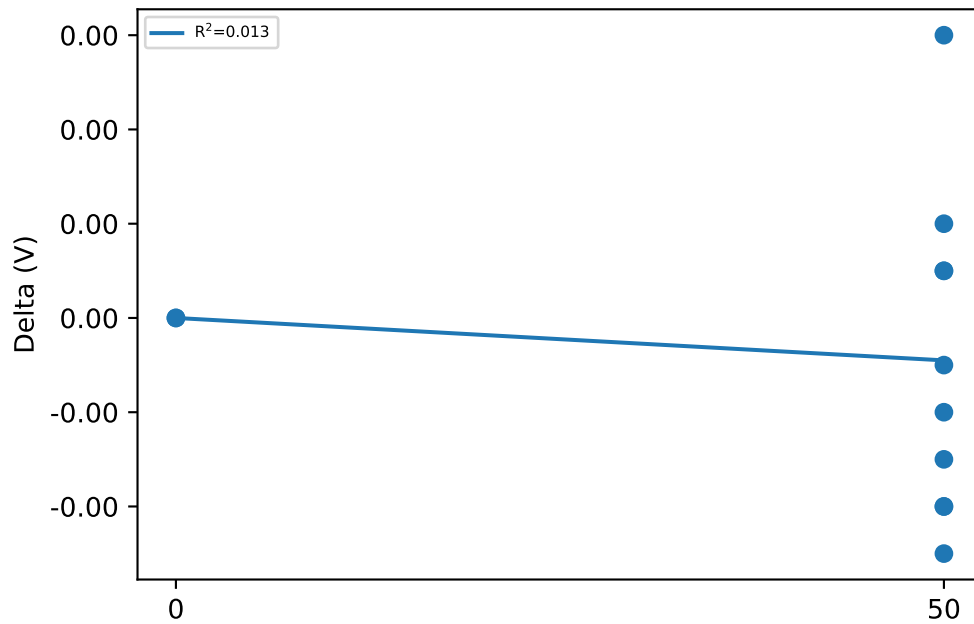
Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5998	0.59995	0.6001	0.00021213	0.5998	0.59995	0.6001	0.00021213	0	0	0	0
50	0.5997	0.59997	0.6003	0.00019465	0.5993	0.59987	0.6005	0.0004644	-0.0005	-0.0001	0.0006	0.00033665

Device Test: 19.65 VREF_25C(VOLTAGE|VREF//12/12/0/1000/5/100kHz//@VREF_25C)



TID krad(si)



TID krad(si)

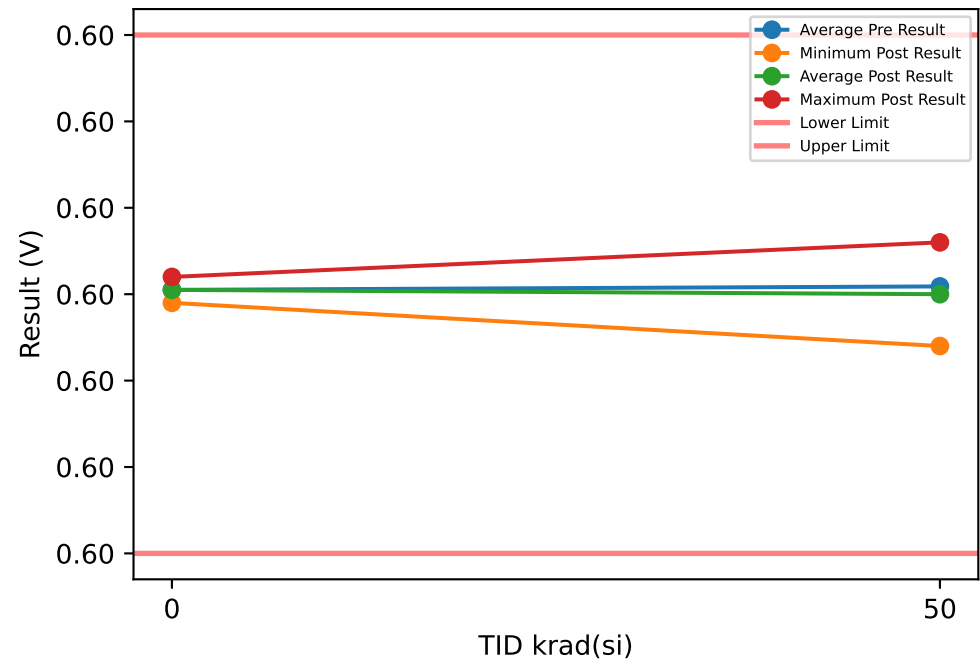
Test Results (Lower Limit = 0.597,
Upper Limit = 0.603 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5999	0.5999	0
2	0	Correlation	0.6002	0.6002	0
4	50	Bias	0.5999	0.5994	-0.0005
6	50	Bias	0.5999	0.5995	-0.0004
7	50	Bias	0.6004	0.6005	0.0001
8	50	Bias	0.6	0.5998	-0.0002
9	50	Bias	0.6	0.5997	-0.0003
11	50	Unbias	0.6002	0.6004	0.0002
12	50	Unbias	0.6003	0.6004	0.0001
13	50	Unbias	0.6002	0.6001	-0.0001
14	50	Unbias	0.5998	0.5994	-0.0004
15	50	Unbias	0.6	0.6006	0.0006

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5999	0.60005	0.6002	0.00021213	0.5999	0.60005	0.6002	0.00021213	0	0	0	0
50	0.5998	0.60007	0.6004	0.00019465	0.5994	0.59998	0.6006	0.00047563	-0.0005	-9e-05	0.0006	0.0003414

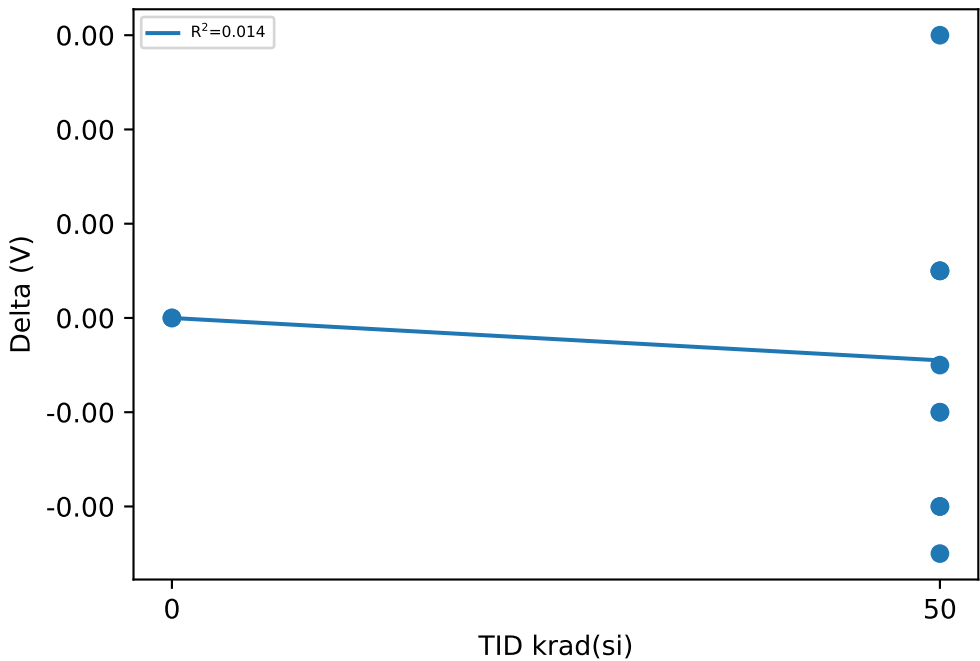
TID vs Result Stats



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5999	0.5999	0
2	0	Correlation	0.6002	0.6002	0
4	50	Bias	0.5999	0.5995	-0.0004
6	50	Bias	0.5999	0.5995	-0.0004
7	50	Bias	0.6004	0.6005	0.0001
8	50	Bias	0.6	0.5998	-0.0002
9	50	Bias	0.6	0.5998	-0.0002
11	50	Unbias	0.6003	0.6004	0.0001
12	50	Unbias	0.6003	0.6004	0.0001
13	50	Unbias	0.6002	0.6001	-0.0001
14	50	Unbias	0.5999	0.5994	-0.0005
15	50	Unbias	0.6	0.6006	0.0006

TID vs Post - Pre Exposure Delta

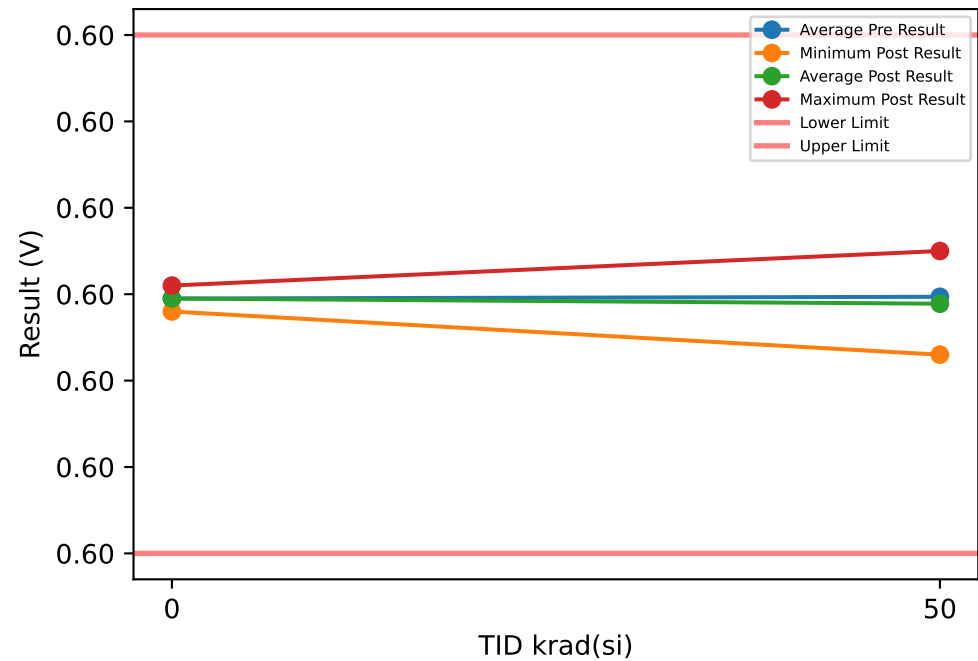


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5999	0.60005	0.6002	0.00021213	0.5999	0.60005	0.6002	0.00021213	0	0	0	0
50	0.5999	0.60009	0.6004	0.0001912	0.5994	0.6	0.6006	0.00045704	-0.0005	-9e-05	0.0006	0.00032813

Device Test: 19.69 VREF_25C(VOLTAGE|VREF//4.5/4.5/0/1000/4.5/500kHz//@VREF_25C)

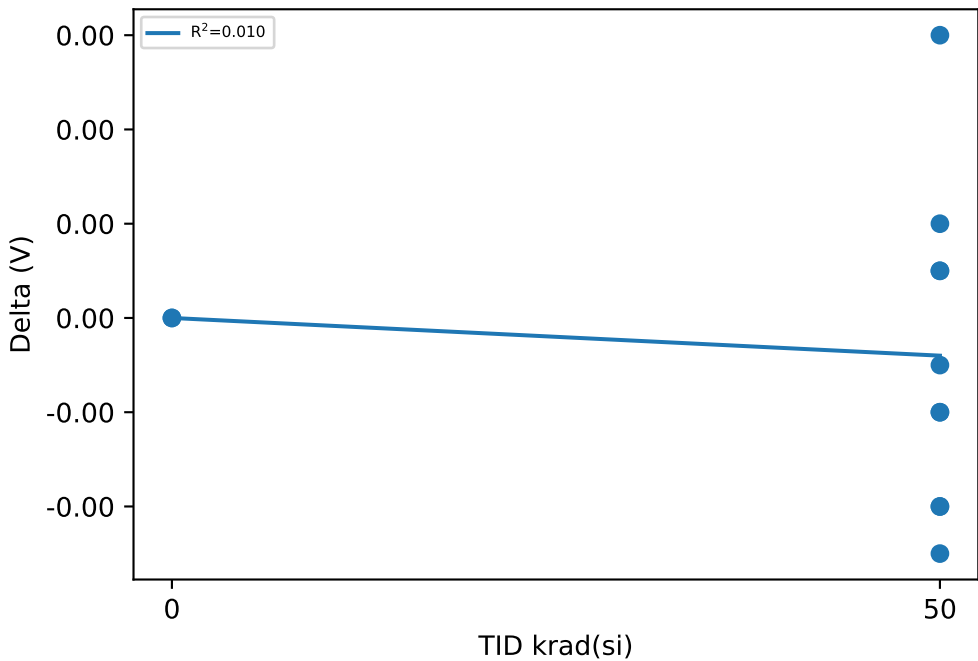
TID vs Result Stats



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5998	0.5998	0
2	0	Correlation	0.6001	0.6001	0
4	50	Bias	0.5998	0.5993	-0.0005
6	50	Bias	0.5998	0.5994	-0.0004
7	50	Bias	0.6003	0.6004	0.0001
8	50	Bias	0.5999	0.5997	-0.0002
9	50	Bias	0.5999	0.5997	-0.0002
11	50	Unbias	0.6001	0.6003	0.0002
12	50	Unbias	0.6002	0.6003	0.0001
13	50	Unbias	0.6001	0.6	-0.0001
14	50	Unbias	0.5997	0.5993	-0.0004
15	50	Unbias	0.5999	0.6005	0.0006

TID vs Post - Pre Exposure Delta

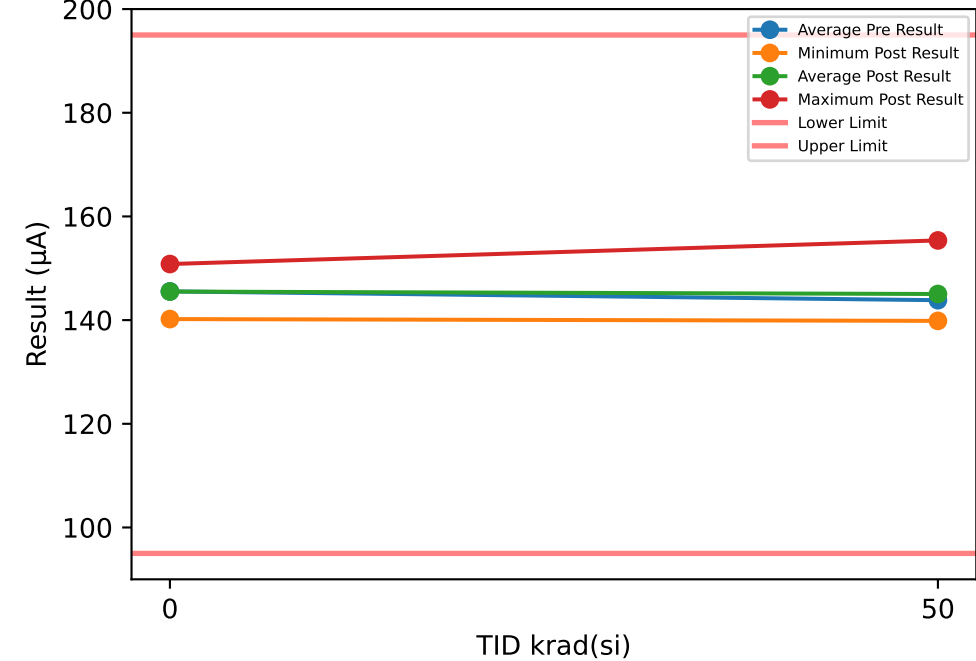


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5998	0.59995	0.6001	0.00021213	0.5998	0.59995	0.6001	0.00021213	0	0	0	0
50	0.5997	0.59997	0.6003	0.00019465	0.5993	0.59989	0.6005	0.00047011	-0.0005	-8e-05	0.0006	0.00033599

Device Test: 19.7 EA_I_SINK(CURRENT|EA_SINK//5/5/0/0/5/500kHz//@EA_I_SINK)

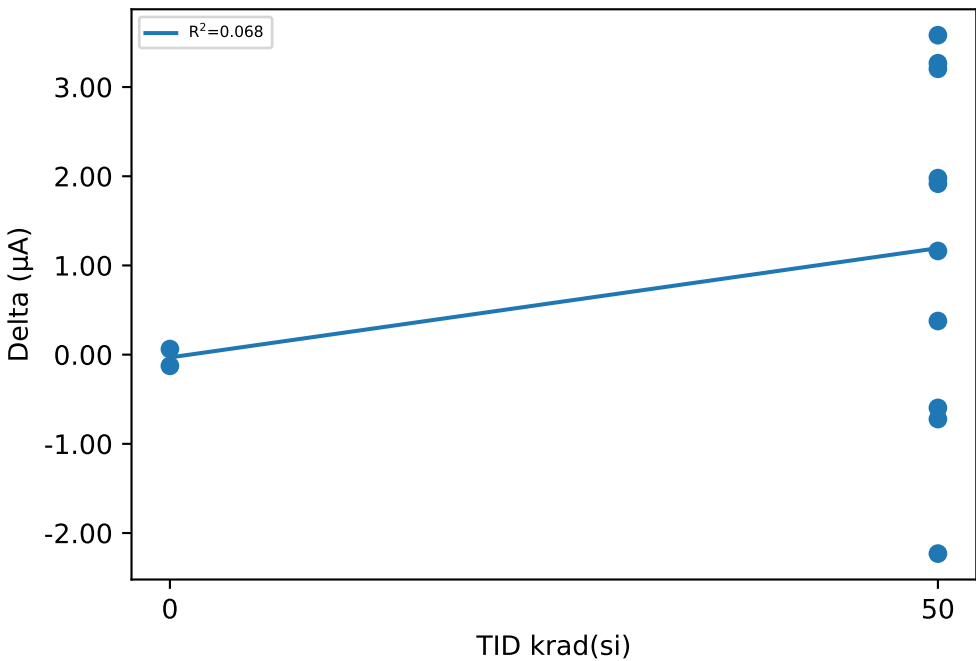
TID vs Result Stats



Test Results (Lower Limit = 95.0, Upper Limit = 195.0 (µA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	150.94	150.82	-0.1257
2	0	Correlation	140.14	140.2	0.0628
4	50	Bias	142.62	144.6	1.9791
6	50	Bias	150.25	148.02	-2.2305
7	50	Bias	139.48	139.85	0.377
8	50	Bias	143.75	146.95	3.2043
9	50	Bias	143.97	143.37	-0.5969
11	50	Unbias	142.68	143.84	1.1623
12	50	Unbias	141.64	140.92	-0.7225
13	50	Unbias	143.44	147.02	3.5813
14	50	Unbias	138.5	140.42	1.9163
15	50	Unbias	152.11	155.37	3.2672

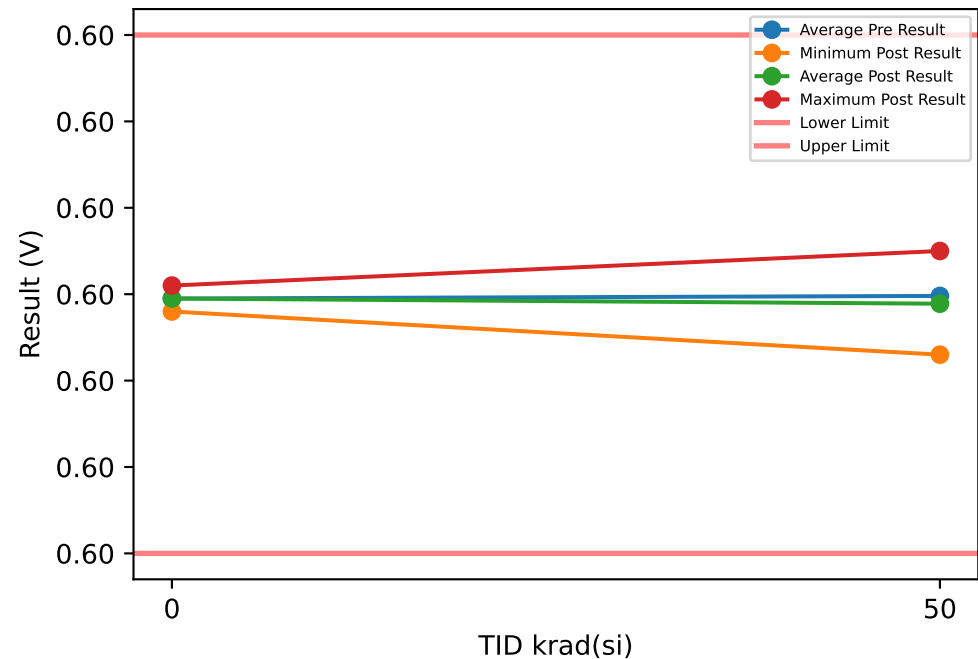
TID vs Post - Pre Exposure Delta



Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	140.14	145.54	150.94	7.6415	140.2	145.51	150.82	7.5082	-0.1257	-0.03145	0.0628	0.13329
50	138.5	143.84	152.11	4.2792	139.85	145.04	155.37	4.6289	-2.2305	1.1938	3.5813	1.9565

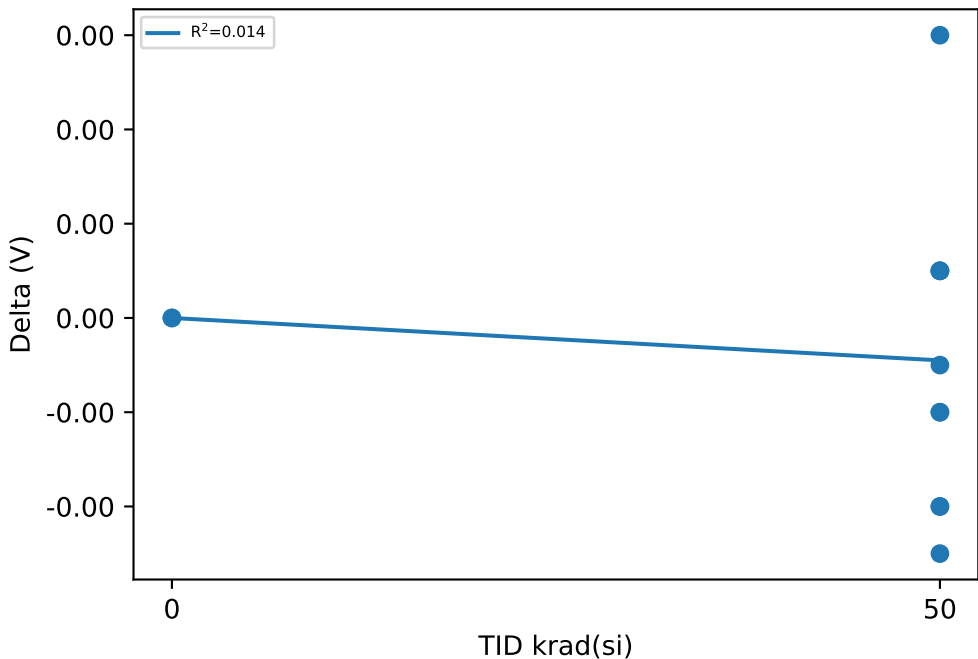
TID vs Result Stats



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5998	0.5998	0
2	0	Correlation	0.6001	0.6001	0
4	50	Bias	0.5998	0.5993	-0.0005
6	50	Bias	0.5998	0.5994	-0.0004
7	50	Bias	0.6003	0.6004	0.0001
8	50	Bias	0.5999	0.5997	-0.0002
9	50	Bias	0.5999	0.5997	-0.0002
11	50	Unbias	0.6002	0.6003	0.0001
12	50	Unbias	0.6002	0.6003	0.0001
13	50	Unbias	0.6001	0.6	-0.0001
14	50	Unbias	0.5997	0.5993	-0.0004
15	50	Unbias	0.5999	0.6005	0.0006

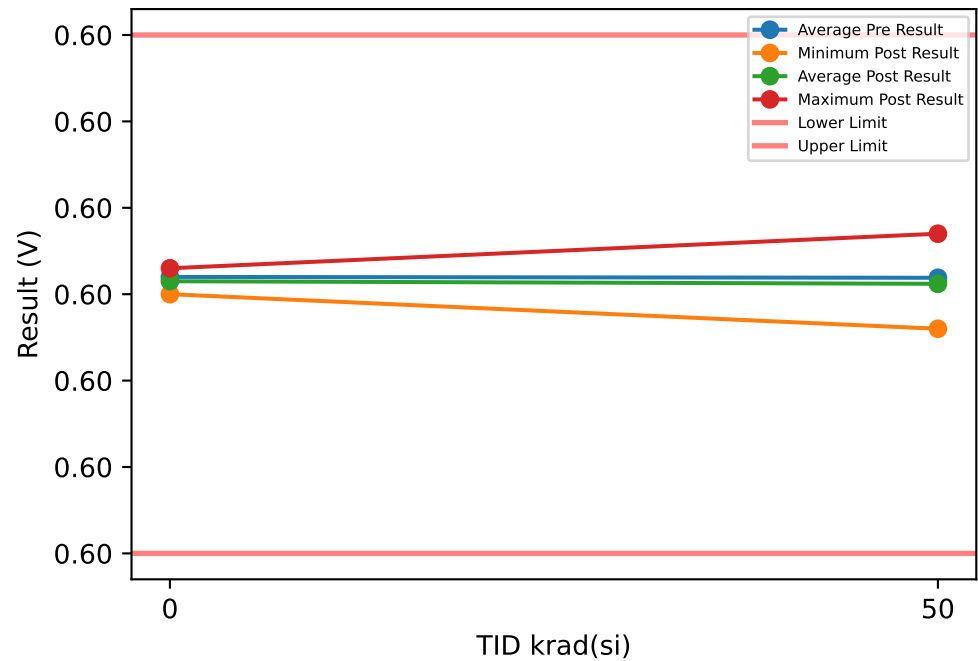
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5998	0.59995	0.6001	0.00021213	0.5998	0.59995	0.6001	0.00021213	0	0	0	0
50	0.5997	0.59998	0.6003	0.0002044	0.5993	0.59989	0.6005	0.00047011	-0.0005	-9e-05	0.0006	0.00032813

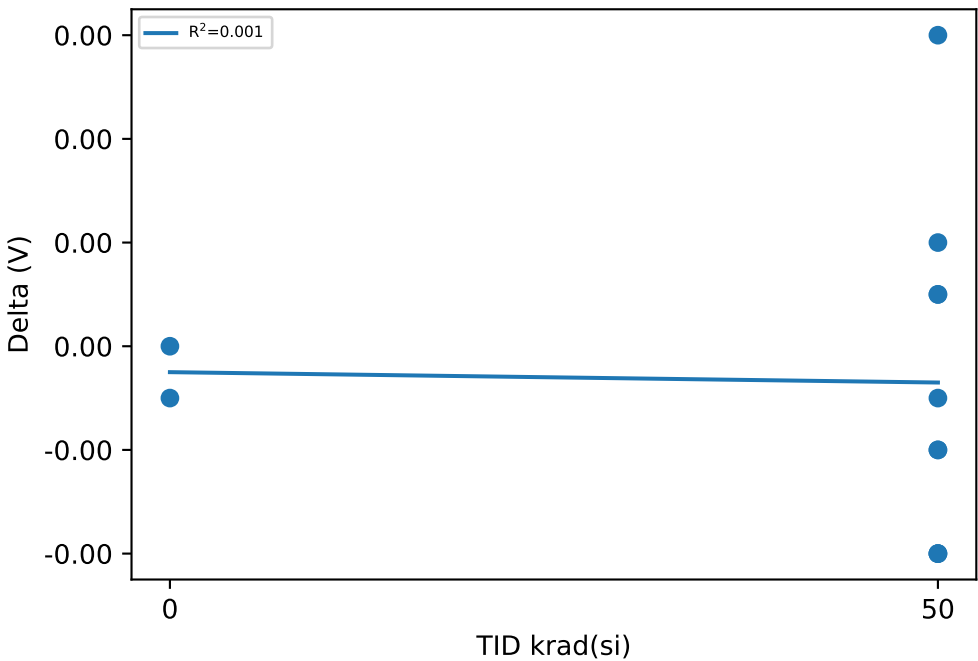
TID vs Result Stats



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.6001	0.6	-0.0001
2	0	Correlation	0.6003	0.6003	0
4	50	Bias	0.6	0.5996	-0.0004
6	50	Bias	0.6	0.5996	-0.0004
7	50	Bias	0.6005	0.6006	0.0001
8	50	Bias	0.6001	0.5999	-0.0002
9	50	Bias	0.6001	0.5999	-0.0002
11	50	Unbias	0.6004	0.6005	0.0001
12	50	Unbias	0.6004	0.6006	0.0002
13	50	Unbias	0.6003	0.6002	-0.0001
14	50	Unbias	0.6	0.5996	-0.0004
15	50	Unbias	0.6001	0.6007	0.0006

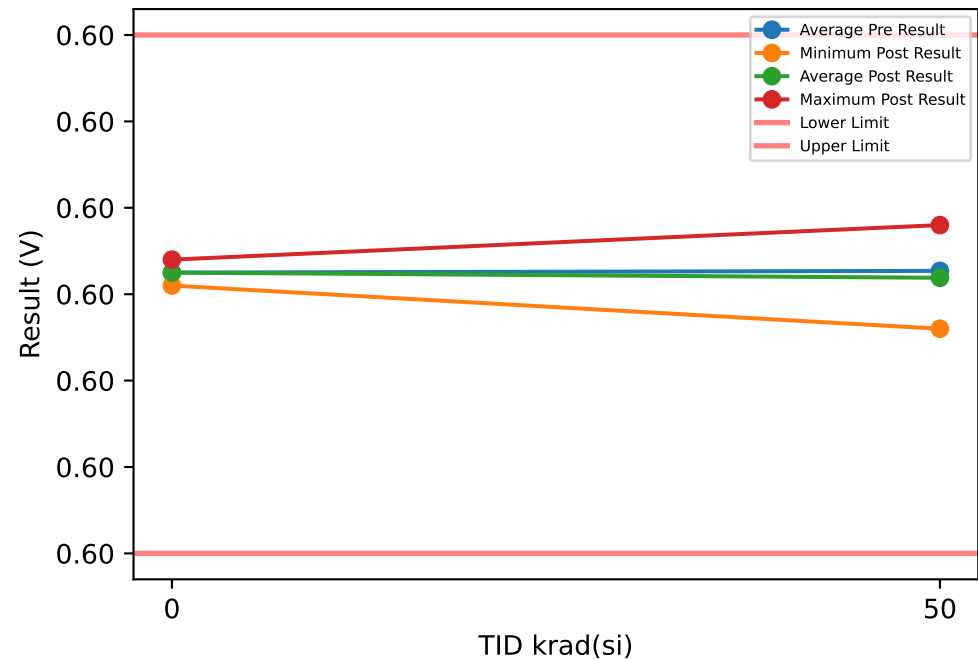
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6001	0.6002	0.6003	0.00014142	0.6	0.60015	0.6003	0.00021213	-0.0001	-5e-05	0	7.0711e-05
50	0.6	0.60019	0.6005	0.0001912	0.5996	0.60012	0.6007	0.00045412	-0.0004	-7e-05	0.0006	0.00032335

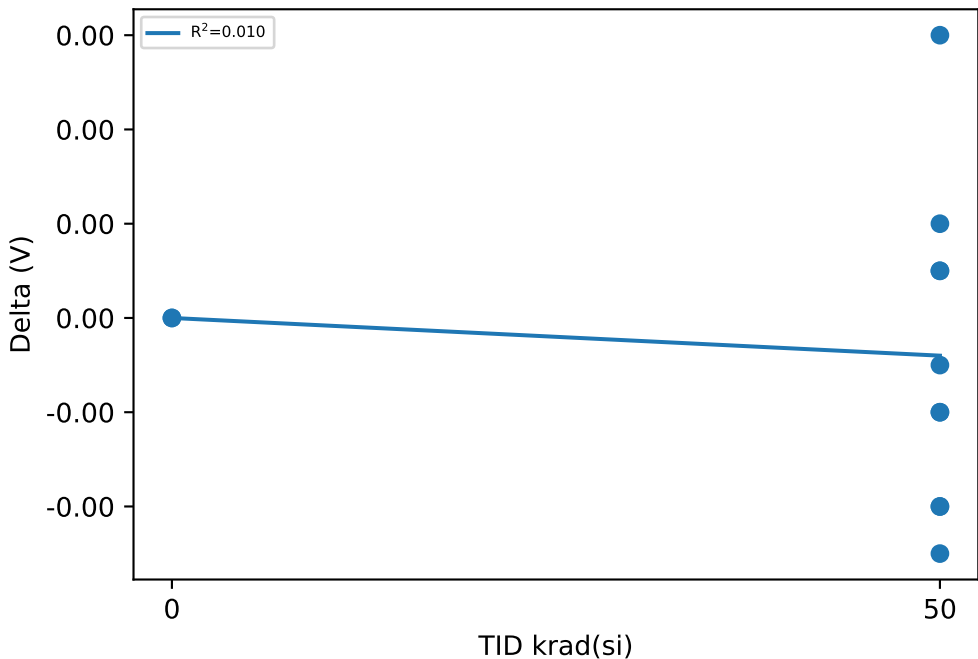
TID vs Result Stats



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.6001	0.6001	0
2	0	Correlation	0.6004	0.6004	0
4	50	Bias	0.6001	0.5996	-0.0005
6	50	Bias	0.6001	0.5997	-0.0004
7	50	Bias	0.6006	0.6007	0.0001
8	50	Bias	0.6002	0.6	-0.0002
9	50	Bias	0.6002	0.6	-0.0002
11	50	Unbias	0.6004	0.6006	0.0002
12	50	Unbias	0.6005	0.6006	0.0001
13	50	Unbias	0.6004	0.6003	-0.0001
14	50	Unbias	0.6	0.5996	-0.0004
15	50	Unbias	0.6002	0.6008	0.0006

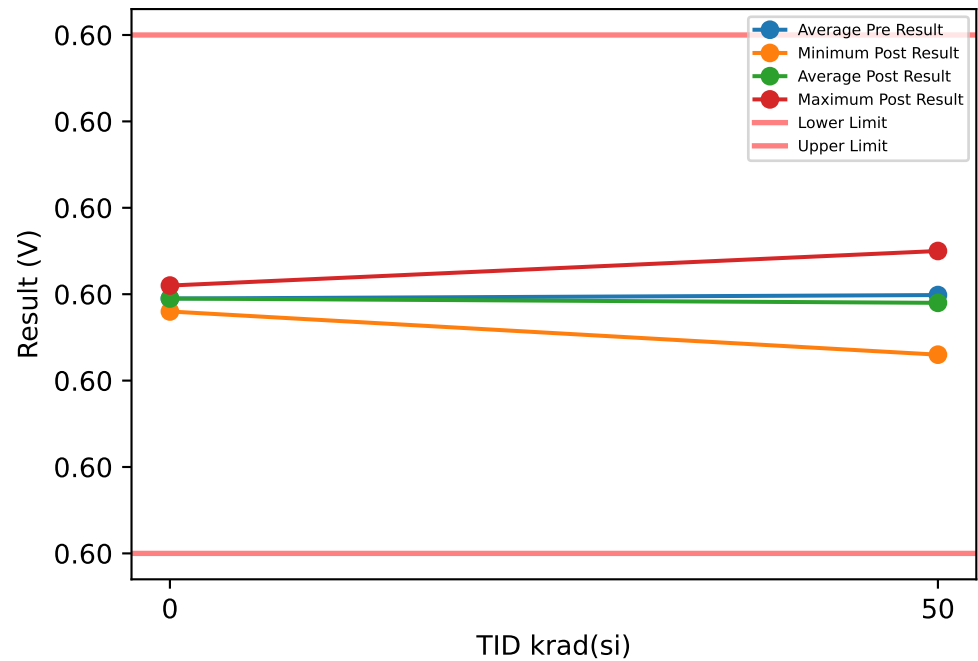
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6001	0.60025	0.6004	0.00021213	0.6001	0.60025	0.6004	0.00021213	0	0	0	0
50	0.6	0.60027	0.6006	0.00019465	0.5996	0.60019	0.6008	0.00047011	-0.0005	-8e-05	0.0006	0.00033599

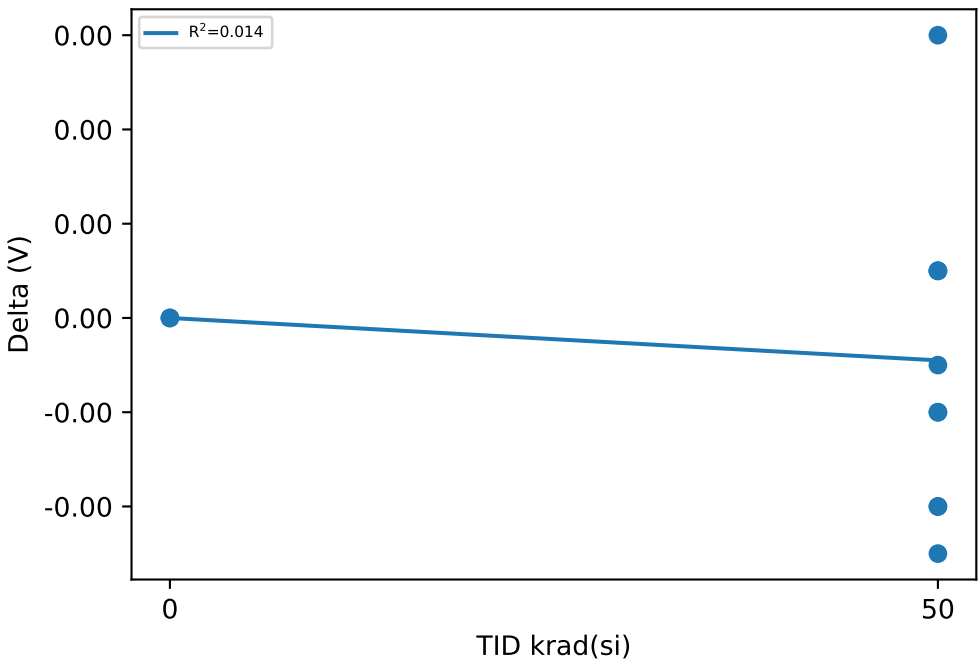
TID vs Result Stats



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5998	0.5998	0
2	0	Correlation	0.6001	0.6001	0
4	50	Bias	0.5998	0.5994	-0.0004
6	50	Bias	0.5999	0.5994	-0.0005
7	50	Bias	0.6003	0.6004	0.0001
8	50	Bias	0.5999	0.5997	-0.0002
9	50	Bias	0.5999	0.5997	-0.0002
11	50	Unbias	0.6002	0.6003	0.0001
12	50	Unbias	0.6002	0.6003	0.0001
13	50	Unbias	0.6001	0.6	-0.0001
14	50	Unbias	0.5997	0.5993	-0.0004
15	50	Unbias	0.5999	0.6005	0.0006

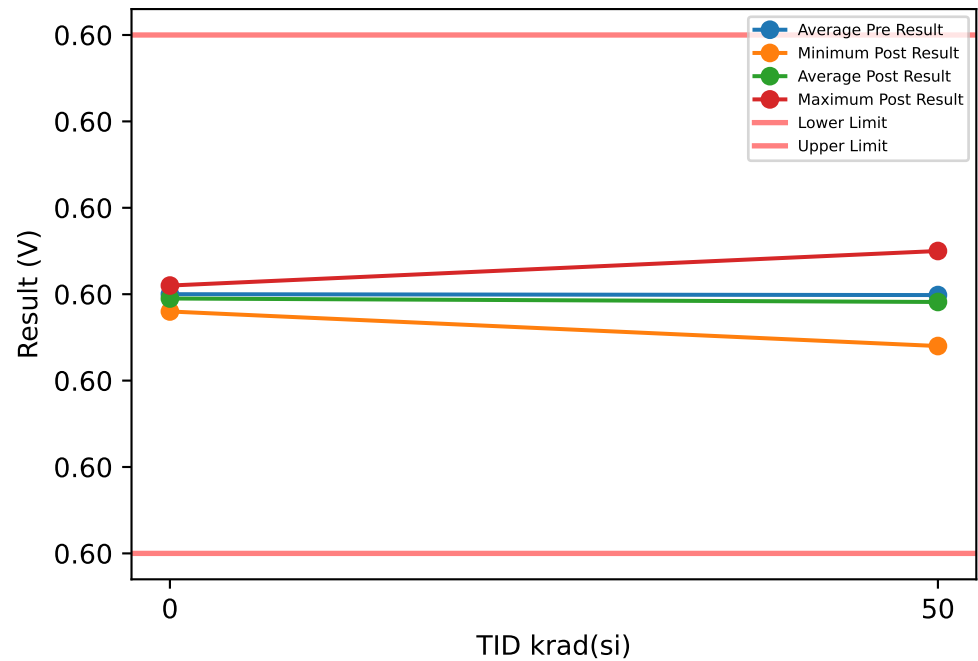
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5998	0.59995	0.6001	0.00021213	0.5998	0.59995	0.6001	0.00021213	0	0	0	0
50	0.5997	0.59999	0.6003	0.00019692	0.5993	0.5999	0.6005	0.00045704	-0.0005	-9e-05	0.0006	0.00032813

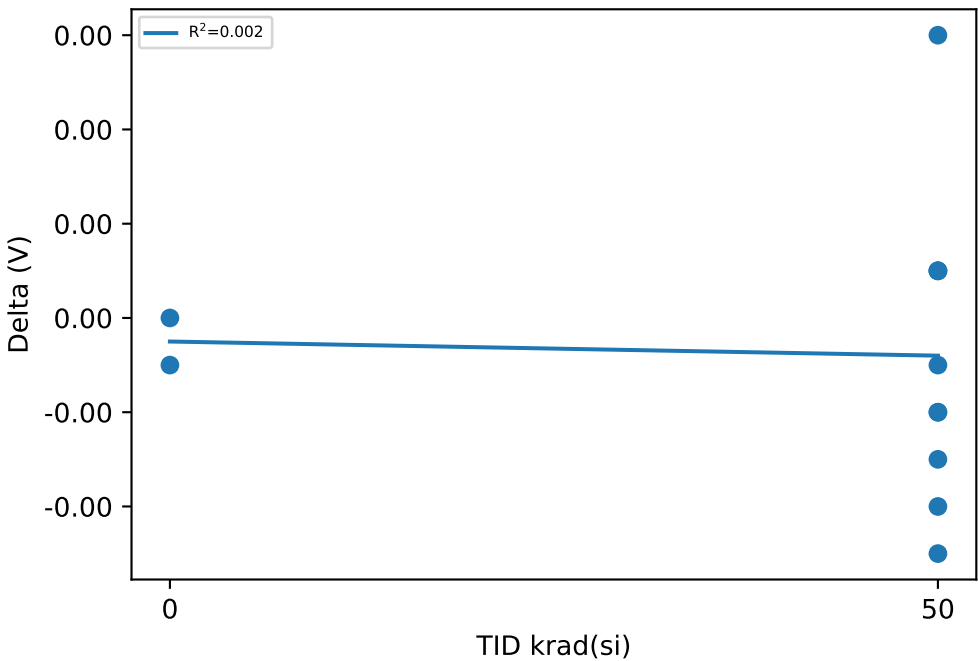
TID vs Result Stats



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5999	0.5998	-0.0001
2	0	Correlation	0.6001	0.6001	0
4	50	Bias	0.5998	0.5994	-0.0004
6	50	Bias	0.5999	0.5994	-0.0005
7	50	Bias	0.6003	0.6004	0.0001
8	50	Bias	0.5999	0.5997	-0.0002
9	50	Bias	0.5999	0.5997	-0.0002
11	50	Unbias	0.6002	0.6003	0.0001
12	50	Unbias	0.6002	0.6003	0.0001
13	50	Unbias	0.6001	0.6	-0.0001
14	50	Unbias	0.5997	0.5994	-0.0003
15	50	Unbias	0.5999	0.6005	0.0006

TID vs Post - Pre Exposure Delta

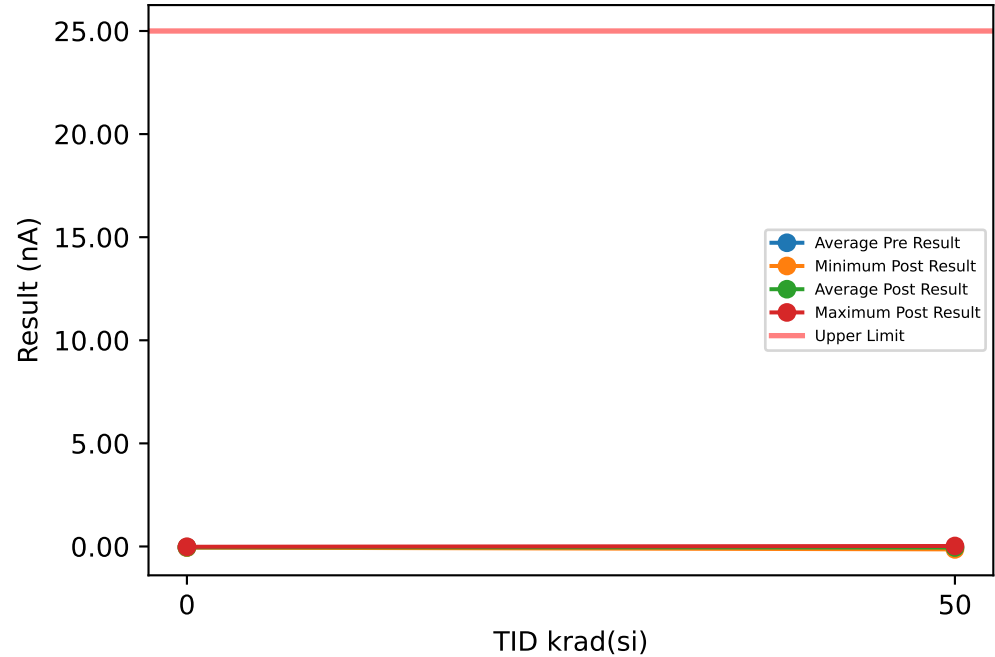


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5999	0.6	0.6001	0.00014142	0.5998	0.59995	0.6001	0.00021213	-0.0001	-5e-05	0	7.0711e-05
50	0.5997	0.59999	0.6003	0.00019692	0.5994	0.59991	0.6005	0.00044335	-0.0005	-8e-05	0.0006	0.00031903

Device Test: 19.8 EA_IB(CURRENT|EA//5/5/0/0/5/500kHz//@EA_IB)

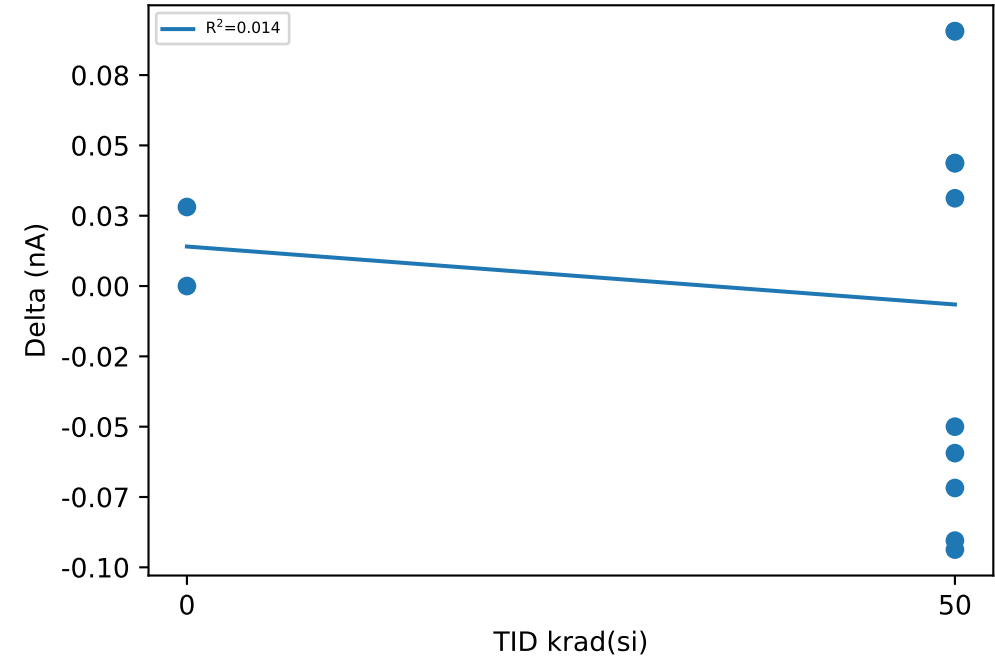
TID vs Result Stats



Test Results (Upper Limit = 25.0 (nA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	-0.042	-0.0139	0.0281
2	0	Correlation	-0.0545	-0.0545	0
4	50	Bias	-0.067	0.0236	0.0906
6	50	Bias	-0.042	-0.1138	-0.0718
7	50	Bias	-0.0482	-0.1076	-0.0594
8	50	Bias	-0.0482	-0.1419	-0.0937
9	50	Bias	-0.0826	-0.0514	0.0312
11	50	Unbias	-0.0607	-0.017	0.0437
12	50	Unbias	-0.0826	0.008	0.0906
13	50	Unbias	0.0392	-0.0108	-0.05
14	50	Unbias	0.0142	-0.0763	-0.0905
15	50	Unbias	-0.0607	-0.017	0.0437

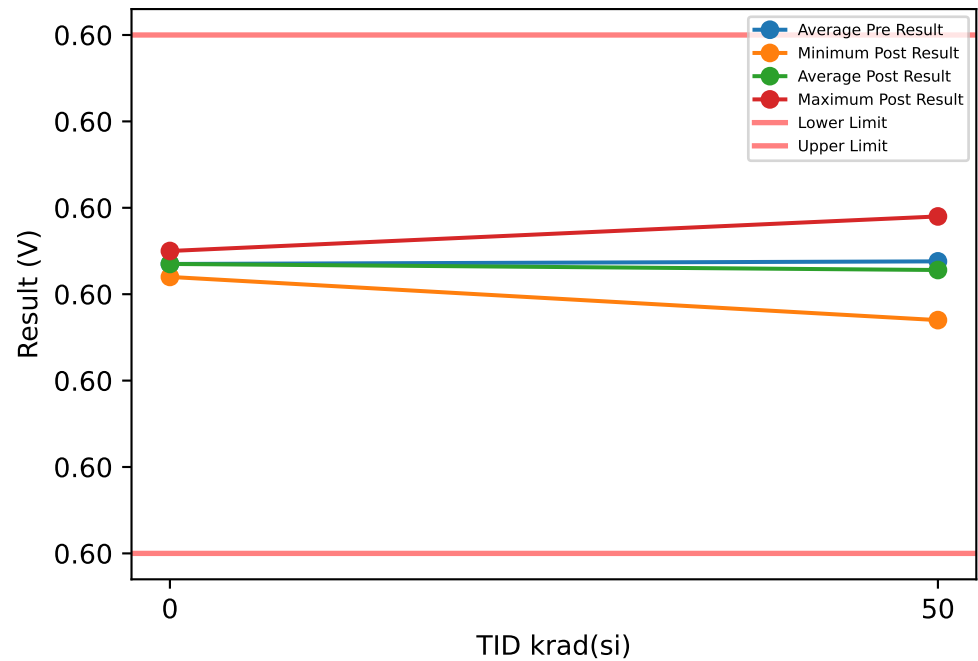
TID vs Post - Pre Exposure Delta



Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.0545	-0.04825	-0.042	0.0088388	-0.0545	-0.0342	-0.0139	0.028709	0	0.01405	0.0281	0.01987
50	-0.0826	-0.04386	0.0392	0.040021	-0.1419	-0.05042	0.0236	0.056785	-0.0937	-0.00656	0.0906	0.073736

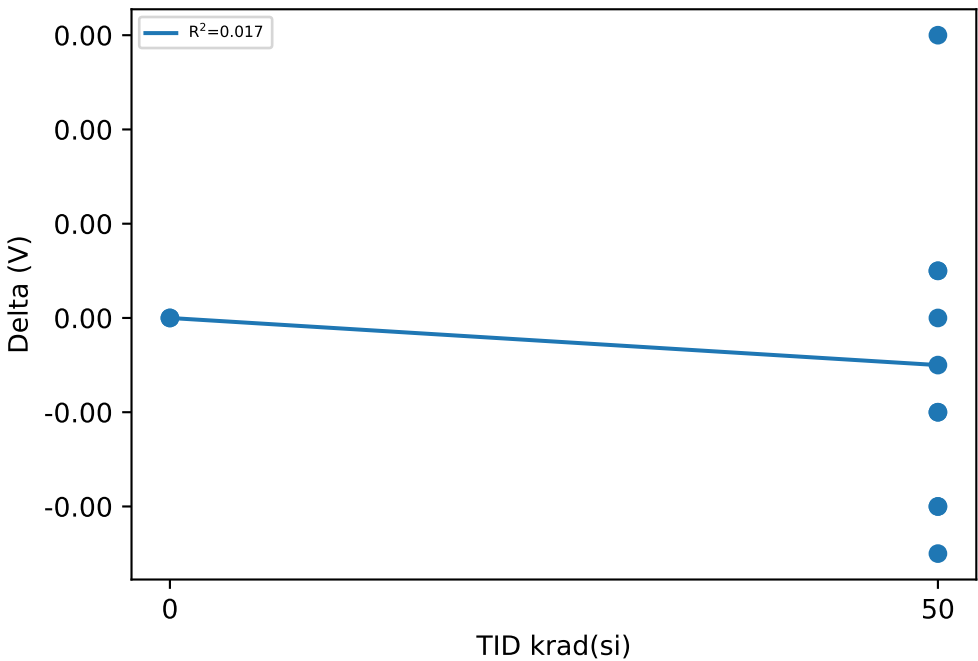
TID vs Result Stats



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.6002	0.6002	0
2	0	Correlation	0.6005	0.6005	0
4	50	Bias	0.6002	0.5997	-0.0005
6	50	Bias	0.6002	0.5998	-0.0004
7	50	Bias	0.6007	0.6007	0
8	50	Bias	0.6003	0.6001	-0.0002
9	50	Bias	0.6003	0.6001	-0.0002
11	50	Unbias	0.6006	0.6007	0.0001
12	50	Unbias	0.6006	0.6007	0.0001
13	50	Unbias	0.6005	0.6004	-0.0001
14	50	Unbias	0.6001	0.5997	-0.0004
15	50	Unbias	0.6003	0.6009	0.0006

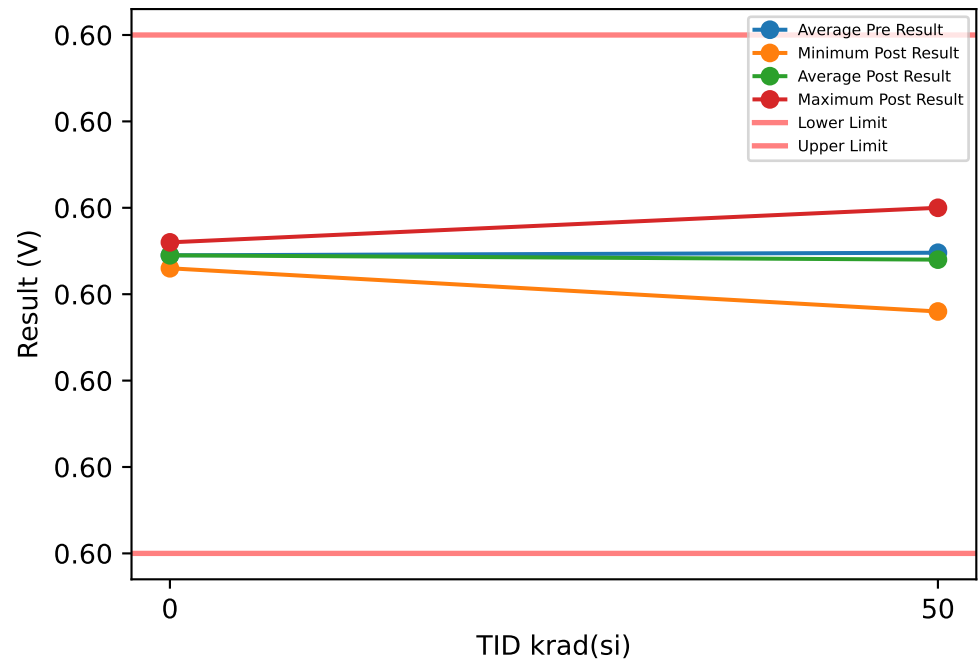
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6002	0.60035	0.6005	0.00021213	0.6002	0.60035	0.6005	0.00021213	0	0	0	0
50	0.6001	0.60038	0.6007	0.0002044	0.5997	0.60028	0.6009	0.00045898	-0.0005	-0.0001	0.0006	0.00032318

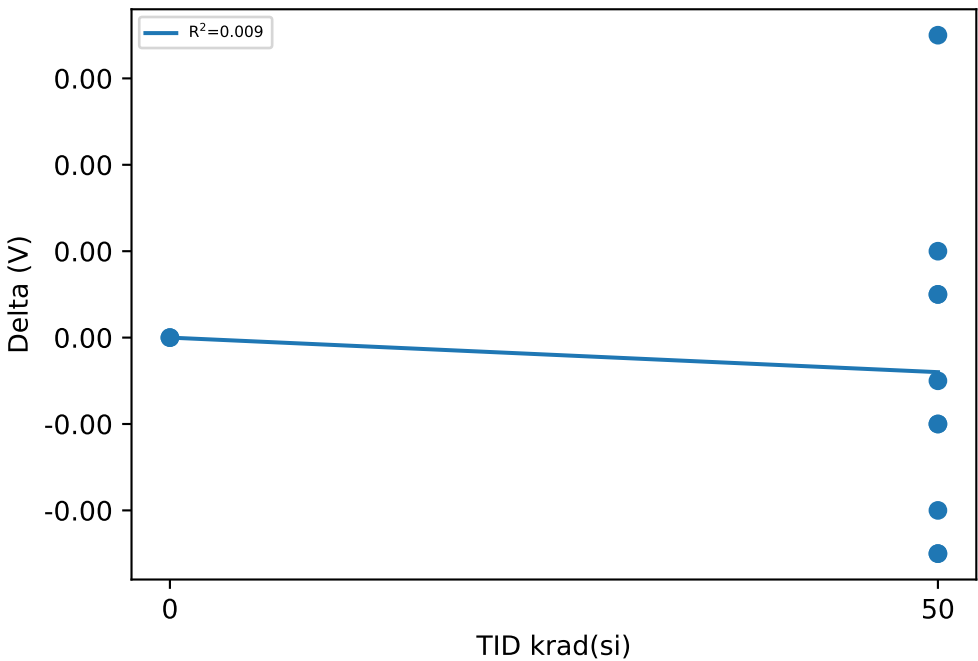
TID vs Result Stats



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.6003	0.6003	0
2	0	Correlation	0.6006	0.6006	0
4	50	Bias	0.6003	0.5998	-0.0005
6	50	Bias	0.6003	0.5999	-0.0004
7	50	Bias	0.6008	0.6009	0.0001
8	50	Bias	0.6004	0.6002	-0.0002
9	50	Bias	0.6004	0.6002	-0.0002
11	50	Unbias	0.6007	0.6008	0.0001
12	50	Unbias	0.6007	0.6009	0.0002
13	50	Unbias	0.6006	0.6005	-0.0001
14	50	Unbias	0.6003	0.5998	-0.0005
15	50	Unbias	0.6003	0.601	0.0007

TID vs Post - Pre Exposure Delta

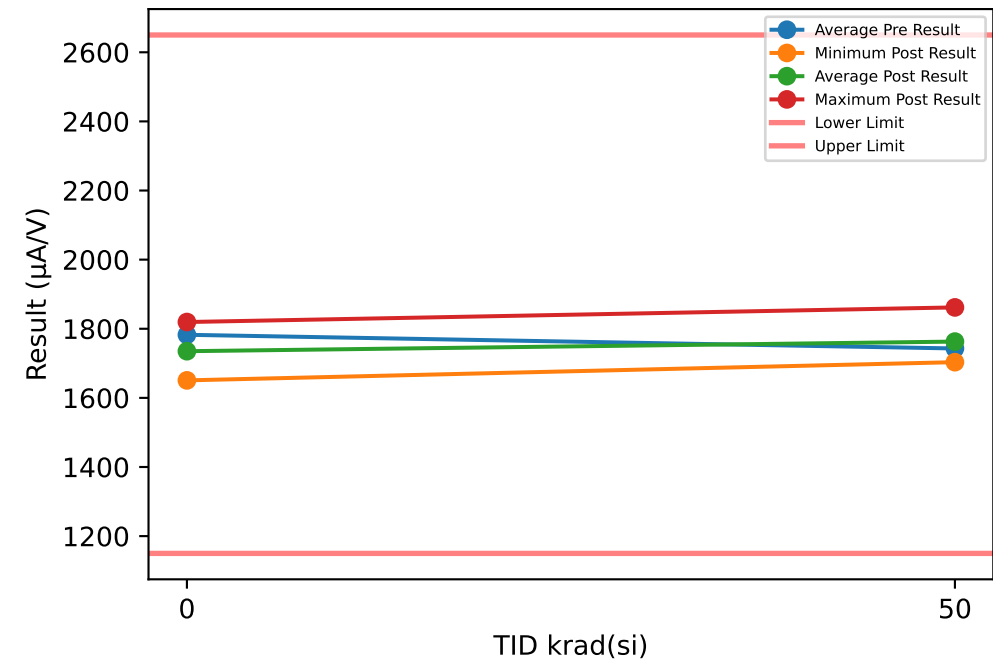


Test Statistics (V)

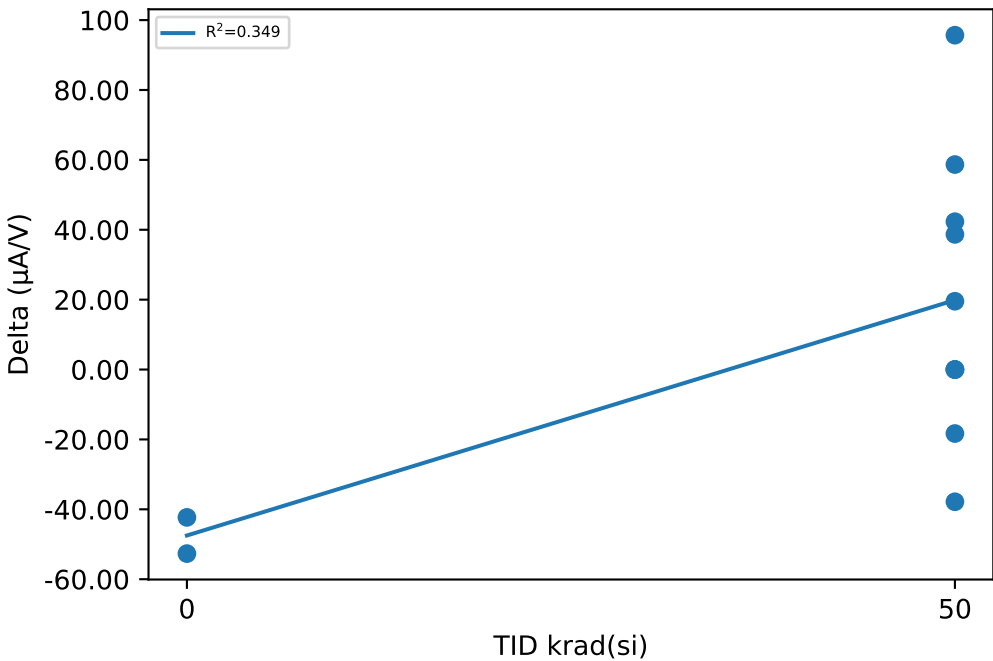
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6003	0.60045	0.6006	0.00021213	0.6003	0.60045	0.6006	0.00021213	0	0	0	0
50	0.6003	0.60048	0.6008	0.00019889	0.5998	0.6004	0.601	0.00048074	-0.0005	-8e-05	0.0007	0.00037059

Device Test: 19.9 EA_GM(LEVEL|TRANSCONDUCTANCE//12/12/0/0/5/500kHz//@EA_GM)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1150.0, Upper Limit = 2650.0 (µA/V))

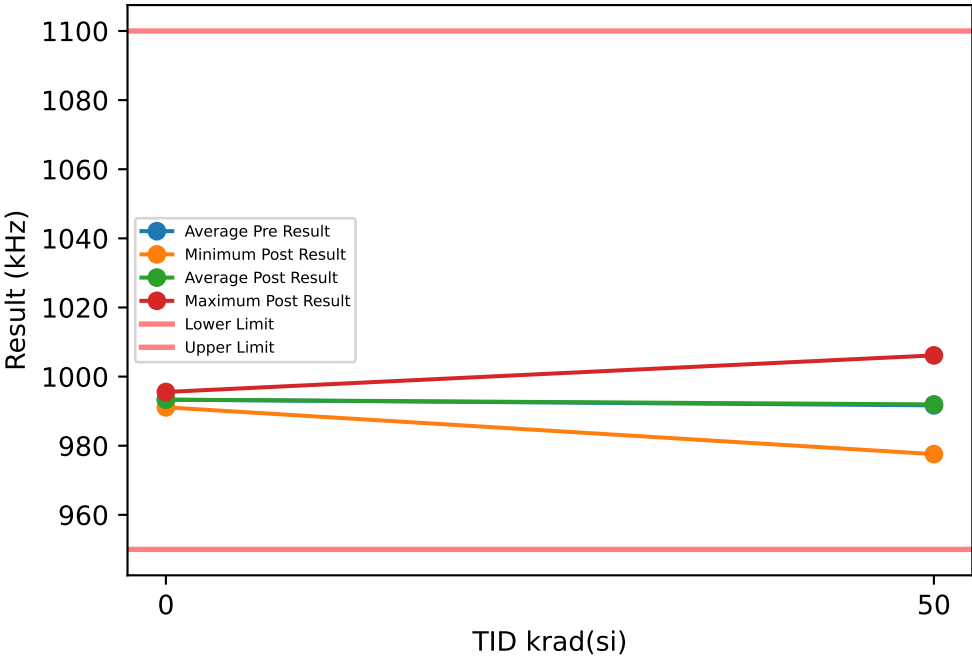
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1861.8	1819.5	-42.31
2	0	Correlation	1703.3	1650.7	-52.672
4	50	Bias	1759.5	1779	19.543
6	50	Bias	1779	1779	0
7	50	Bias	1703.3	1703.3	0.0086
8	50	Bias	1703.3	1799	95.68
9	50	Bias	1721.6	1703.3	-18.309
11	50	Unbias	1740.4	1799	58.663
12	50	Unbias	1759.5	1721.6	-37.835
13	50	Unbias	1740.4	1779	38.681
14	50	Unbias	1703.3	1703.3	0
15	50	Unbias	1819.5	1861.8	42.31

Test Statistics (µA/V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1703.3	1782.5	1861.8	112.04	1650.7	1735.1	1819.5	119.37	-52.672	-47.491	-42.31	7.327
50	1703.3	1743	1819.5	37.83	1703.3	1762.9	1861.8	53.241	-37.835	19.874	95.68	39.555

Device Test: 20.101 FSW_EXT_RT_D(LEVEL|FREQ/RT/14/14/0/1000/5/1MHz//@FSW_EXT_RT_D)

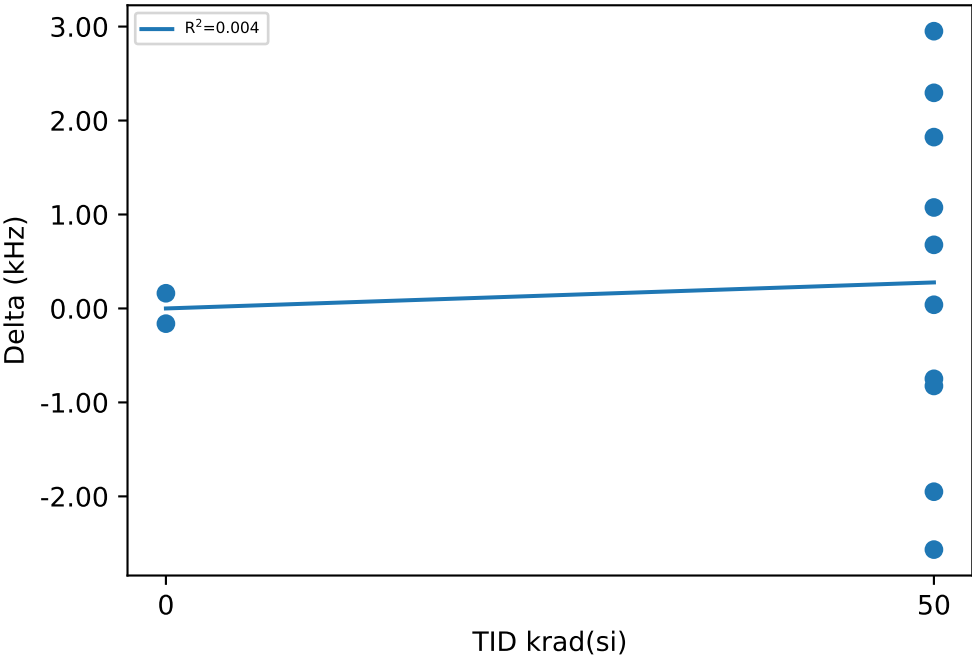
TID vs Result Stats



Test Results (Lower Limit = 950.0, Upper Limit = 1100.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	991.27	991.11	-0.1617
2	0	Correlation	995.39	995.55	0.1617
4	50	Bias	993.84	993.01	-0.8247
6	50	Bias	978.32	977.57	-0.7487
7	50	Bias	991.79	991.83	0.0393
8	50	Bias	981.31	983.13	1.8236
9	50	Bias	989.01	991.31	2.2949
11	50	Unbias	1005.5	1006.1	0.6772
12	50	Unbias	999.36	1000.4	1.0747
13	50	Unbias	995.51	992.94	-2.5664
14	50	Unbias	986.43	989.38	2.9508
15	50	Unbias	995.77	993.82	-1.9503

TID vs Post - Pre Exposure Delta

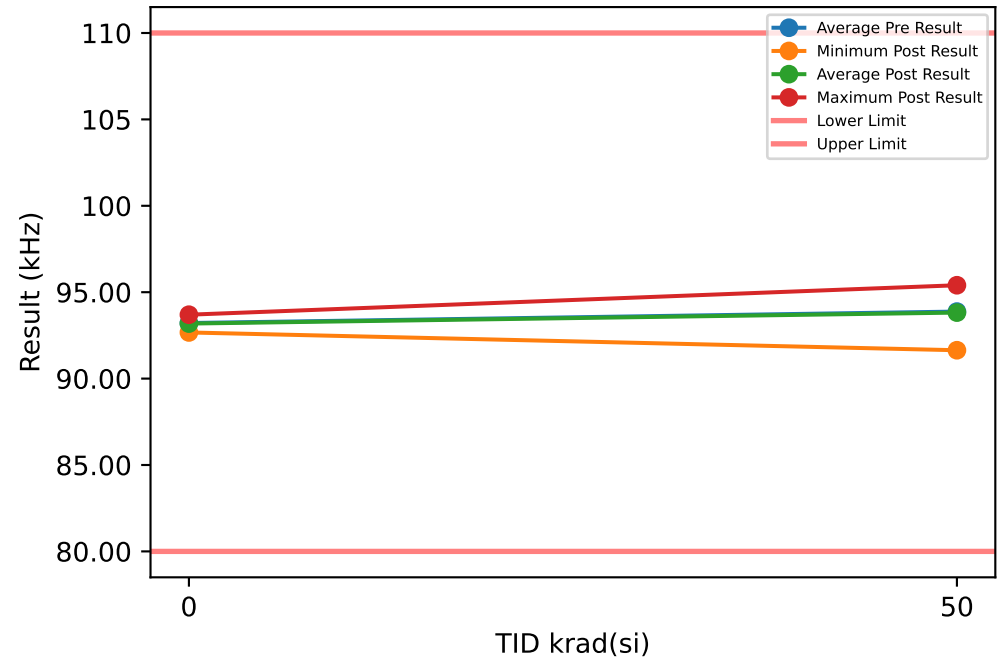


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	991.27	993.33	995.39	2.9129	991.11	993.33	995.55	3.1415	-0.1617	-5.6843e-14	0.1617	0.22868
50	978.32	991.68	1005.5	8.2022	977.57	991.96	1006.1	7.9599	-2.5664	0.27704	2.9508	1.819

Device Test: 20.15 FSW_EXT_RT_A(LEVEL|FREQ/RT/4.5/4.5/0/0/4.5/100kHz//@FSW_EXT_RT_A)

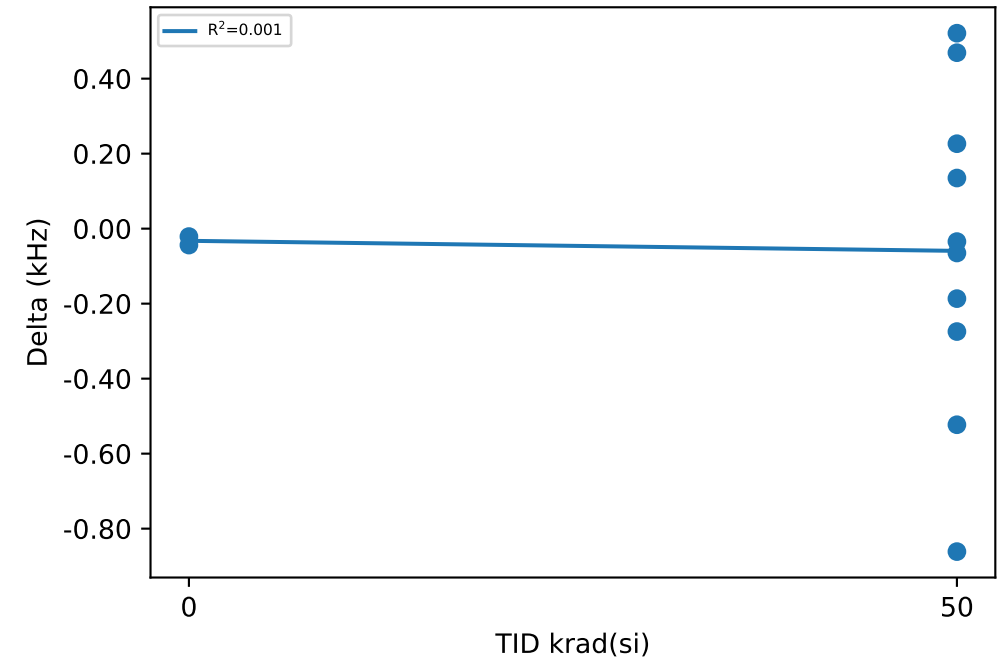
TID vs Result Stats



Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	92.714	92.67	-0.0438
2	0	Correlation	93.719	93.698	-0.0211
4	50	Bias	95.009	94.823	-0.1866
6	50	Bias	91.706	91.641	-0.0649
7	50	Bias	94.521	94.487	-0.0345
8	50	Bias	92.359	92.494	0.135
9	50	Bias	93.981	94.502	0.5212
11	50	Unbias	95.677	95.402	-0.2744
12	50	Unbias	94.616	94.842	0.2265
13	50	Unbias	93.411	92.55	-0.8612
14	50	Unbias	92.983	93.452	0.4692
15	50	Unbias	94.523	94	-0.5229

TID vs Post - Pre Exposure Delta

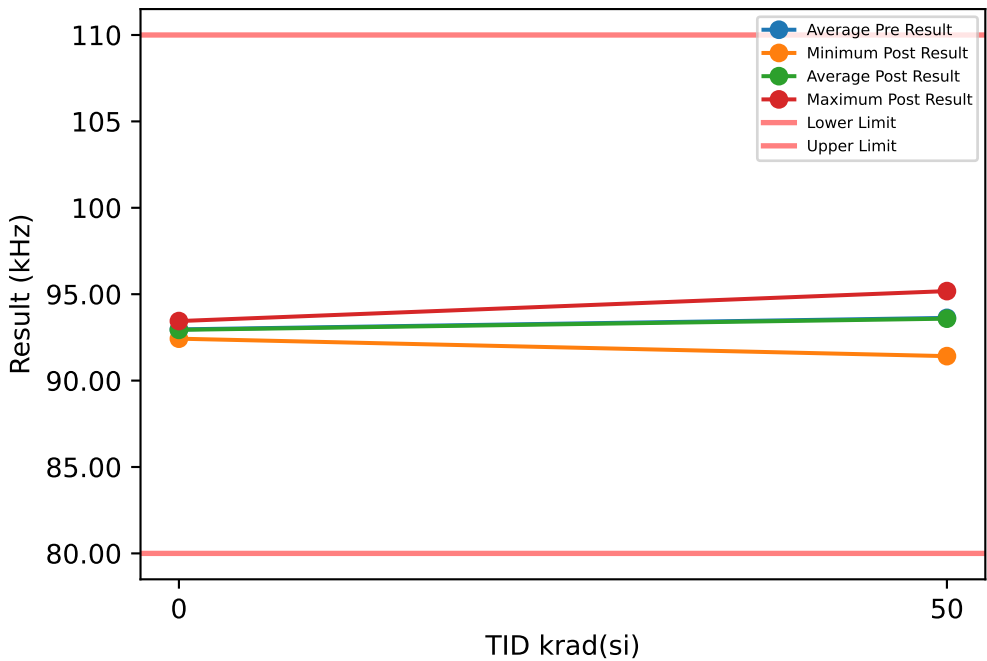


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	92.714	93.216	93.719	0.71043	92.67	93.184	93.698	0.72648	-0.0438	-0.03245	-0.0211	0.016051
50	91.706	93.879	95.677	1.2446	91.641	93.819	95.402	1.236	-0.8612	-0.05926	0.5212	0.42906

Device Test: 20.19 FSW_EXT_RT_A(LEVEL|FREQ/RT/5/5/0/0/5/100kHz//@FSW_EXT_RT_A)

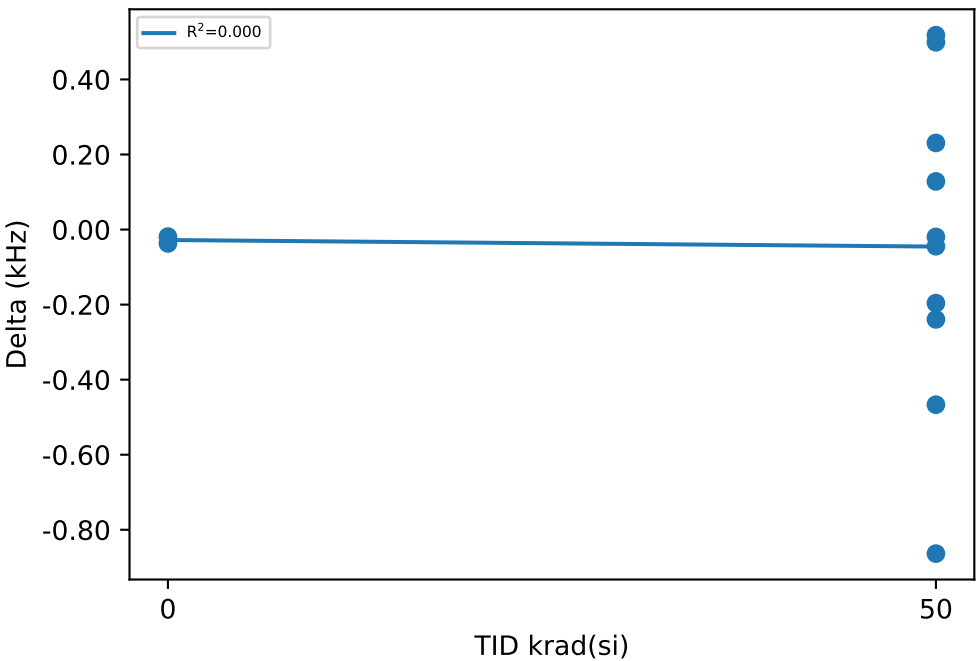
TID vs Result Stats



Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	92.463	92.426	-0.037
2	0	Correlation	93.463	93.445	-0.0188
4	50	Bias	94.775	94.579	-0.196
6	50	Bias	91.46	91.416	-0.0445
7	50	Bias	94.252	94.233	-0.0196
8	50	Bias	92.106	92.234	0.1283
9	50	Bias	93.752	94.27	0.5179
11	50	Unbias	95.418	95.179	-0.2394
12	50	Unbias	94.362	94.593	0.2308
13	50	Unbias	93.167	92.304	-0.8635
14	50	Unbias	92.738	93.237	0.499
15	50	Unbias	94.257	93.791	-0.4667

TID vs Post - Pre Exposure Delta

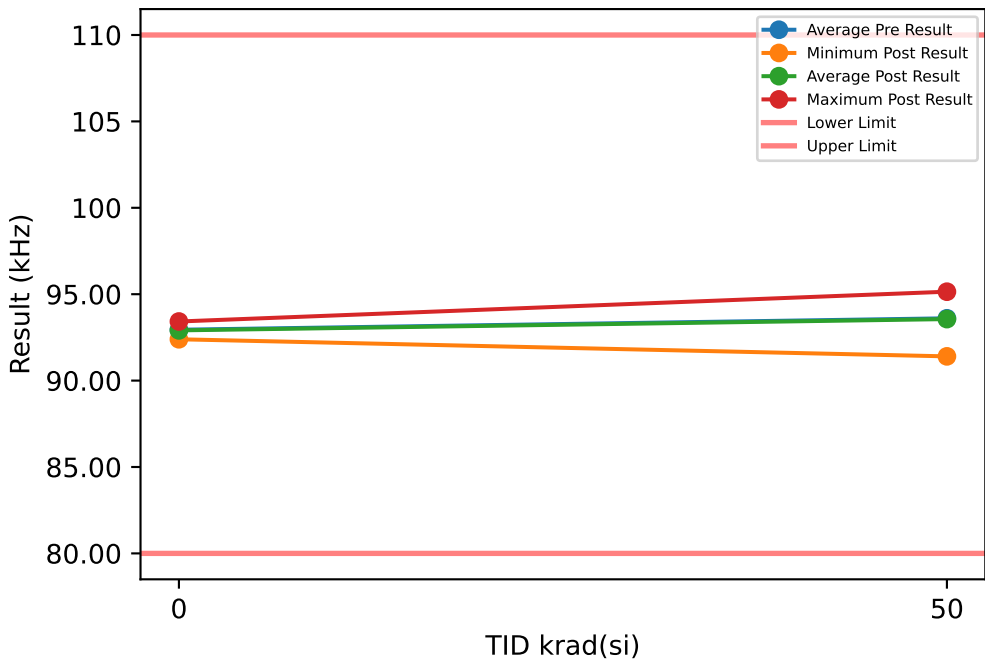


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	92.463	92.963	93.463	0.70746	92.426	92.935	93.445	0.72033	-0.037	-0.0279	-0.0188	0.012869
50	91.46	93.629	95.418	1.242	91.416	93.584	95.179	1.2369	-0.8635	-0.04537	0.5179	0.4253

Device Test: 20.23 FSW_EXT_RT_A(LEVEL|FREQ/RT/12/12/0/0/5/100kHz//@FSW_EXT_RT_A)

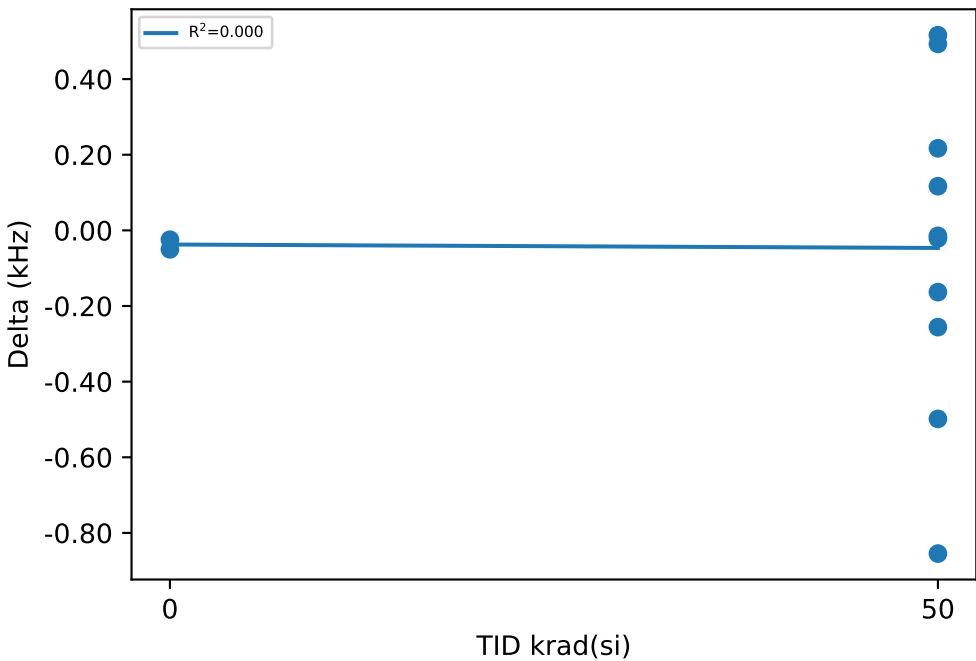
TID vs Result Stats



Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	92.442	92.392	-0.0501
2	0	Correlation	93.445	93.42	-0.0247
4	50	Bias	94.738	94.575	-0.1633
6	50	Bias	91.423	91.402	-0.021
7	50	Bias	94.239	94.224	-0.0145
8	50	Bias	92.091	92.208	0.1168
9	50	Bias	93.727	94.243	0.5161
11	50	Unbias	95.4	95.144	-0.2558
12	50	Unbias	94.344	94.561	0.2171
13	50	Unbias	93.129	92.274	-0.8547
14	50	Unbias	92.708	93.201	0.4931
15	50	Unbias	94.253	93.755	-0.4985

TID vs Post - Pre Exposure Delta

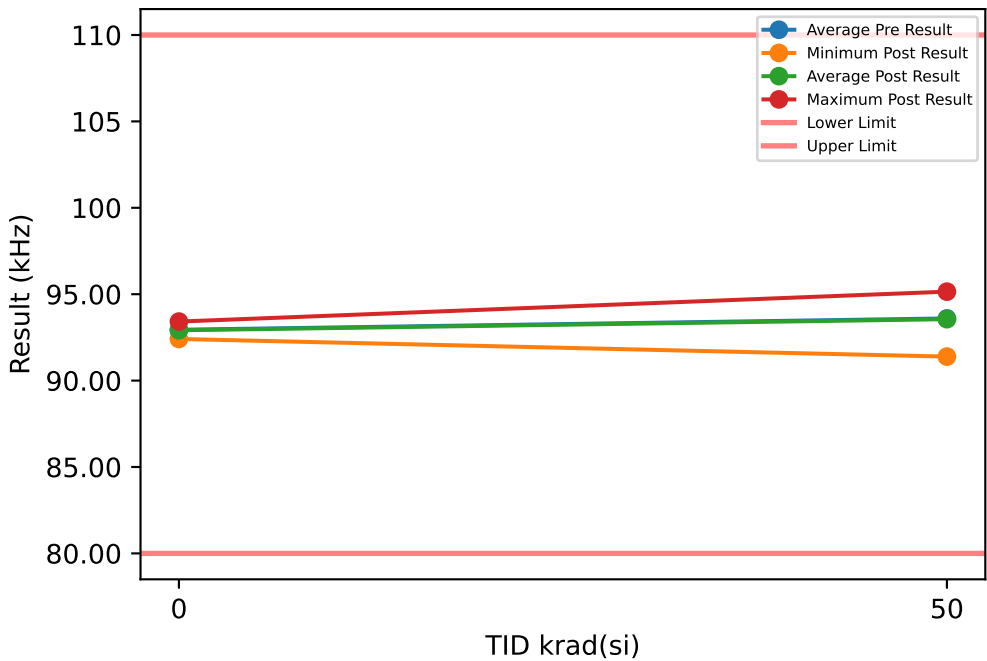


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	92.442	92.943	93.445	0.70909	92.392	92.906	93.42	0.72705	-0.0501	-0.0374	-0.0247	0.017961
50	91.423	93.605	95.4	1.2459	91.402	93.559	95.144	1.2362	-0.8547	-0.04647	0.5161	0.42432

Device Test: 20.27 FSW_EXT_RT_A(LEVEL|FREQ/RT/14/14/0/0/5/100kHz//@FSW_EXT_RT_A)

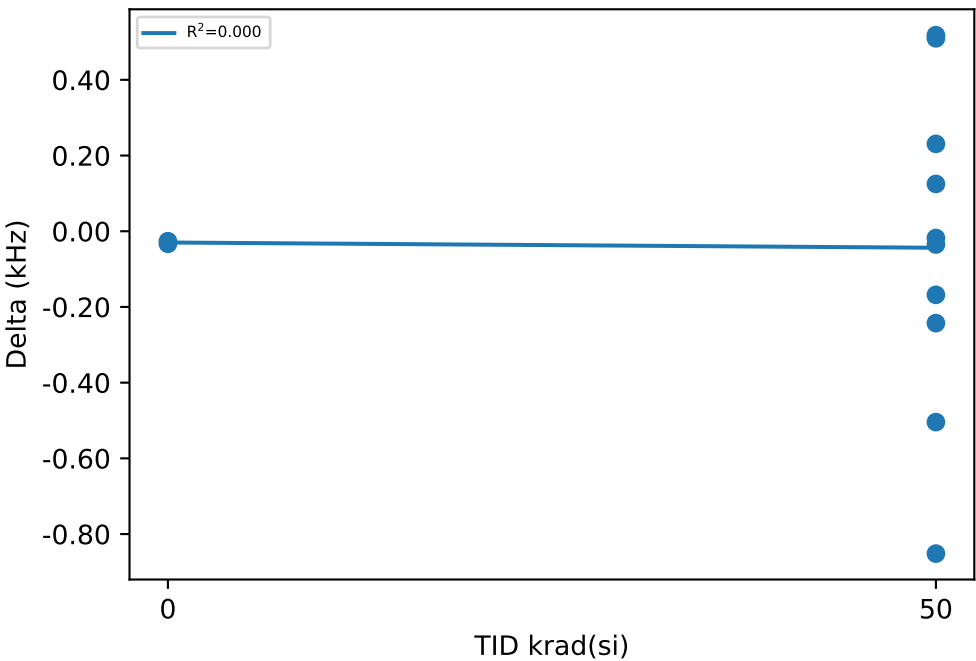
TID vs Result Stats



Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	92.435	92.409	-0.0264
2	0	Correlation	93.449	93.416	-0.0331
4	50	Bias	94.728	94.56	-0.168
6	50	Bias	91.424	91.389	-0.035
7	50	Bias	94.233	94.215	-0.0179
8	50	Bias	92.085	92.21	0.125
9	50	Bias	93.721	94.239	0.5179
11	50	Unbias	95.39	95.148	-0.2427
12	50	Unbias	94.327	94.558	0.2308
13	50	Unbias	93.128	92.276	-0.8516
14	50	Unbias	92.697	93.207	0.5097
15	50	Unbias	94.245	93.741	-0.5042

TID vs Post - Pre Exposure Delta

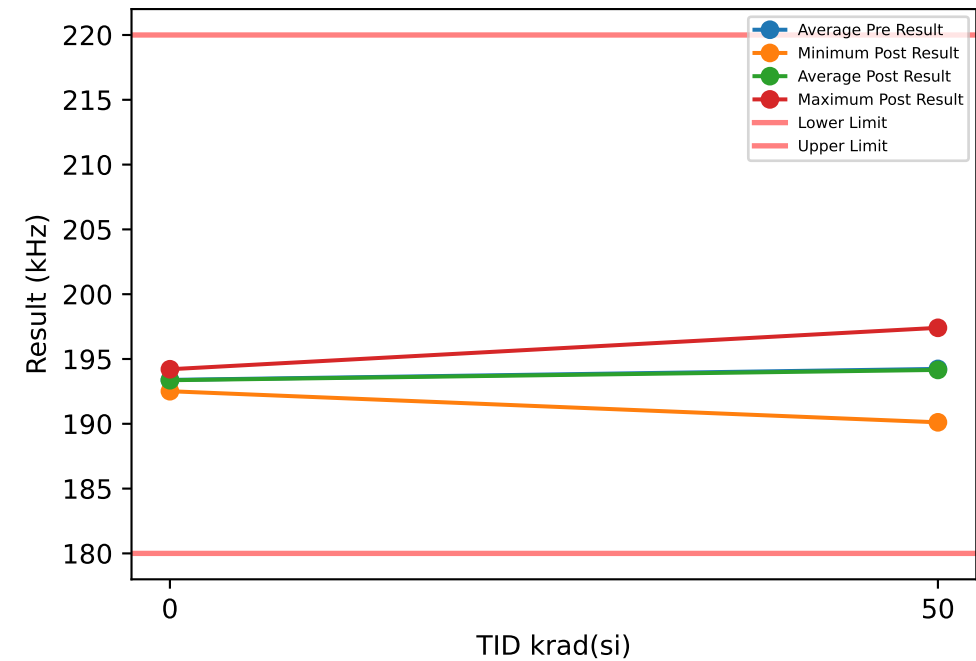


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	92.435	92.942	93.449	0.71672	92.409	92.912	93.416	0.71199	-0.0331	-0.02975	-0.0264	0.0047376
50	91.424	93.598	95.39	1.243	91.389	93.554	95.148	1.2358	-0.8516	-0.0436	0.5179	0.42766

Device Test: 20.31 FSW_EXT_RT_B(LEVEL|FREQ/RT/4.5/4.5/0/0/4.5/200kHz//@FSW_EXT_RT_B)

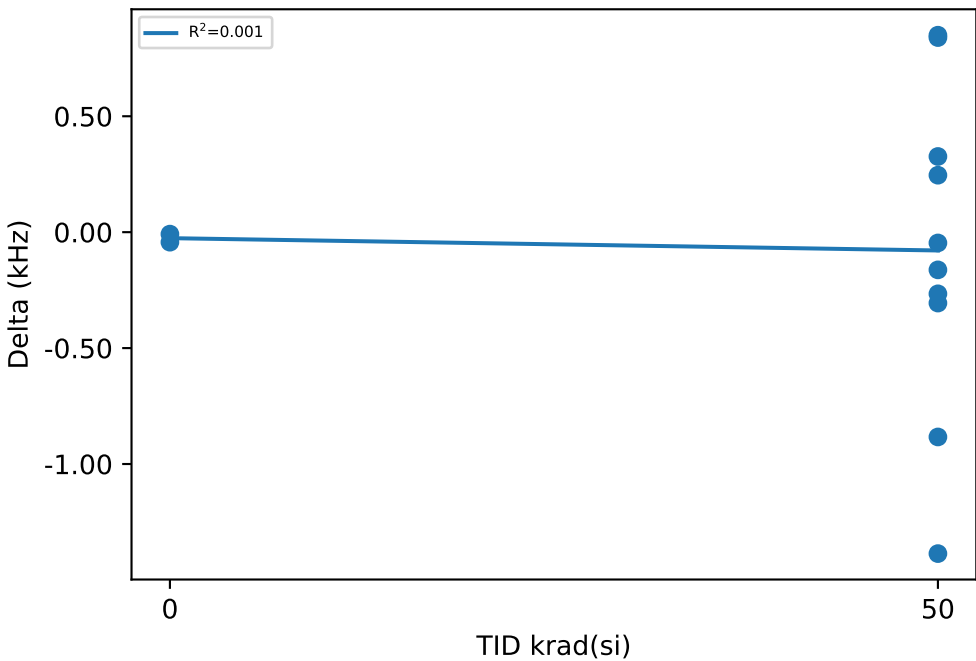
TID vs Result Stats



Test Results (Lower Limit = 180.0, Upper Limit = 220.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	192.56	192.51	-0.0432
2	0	Correlation	194.22	194.21	-0.0084
4	50	Bias	195.76	195.45	-0.3058
6	50	Bias	190.28	190.11	-0.1626
7	50	Bias	194.91	194.87	-0.0465
8	50	Bias	191.6	191.85	0.2457
9	50	Bias	194.14	194.99	0.8496
11	50	Unbias	197.67	197.41	-0.2659
12	50	Unbias	195.91	196.24	0.3265
13	50	Unbias	194.04	192.65	-1.3864
14	50	Unbias	192.7	193.54	0.8394
15	50	Unbias	195.33	194.45	-0.8833

TID vs Post - Pre Exposure Delta

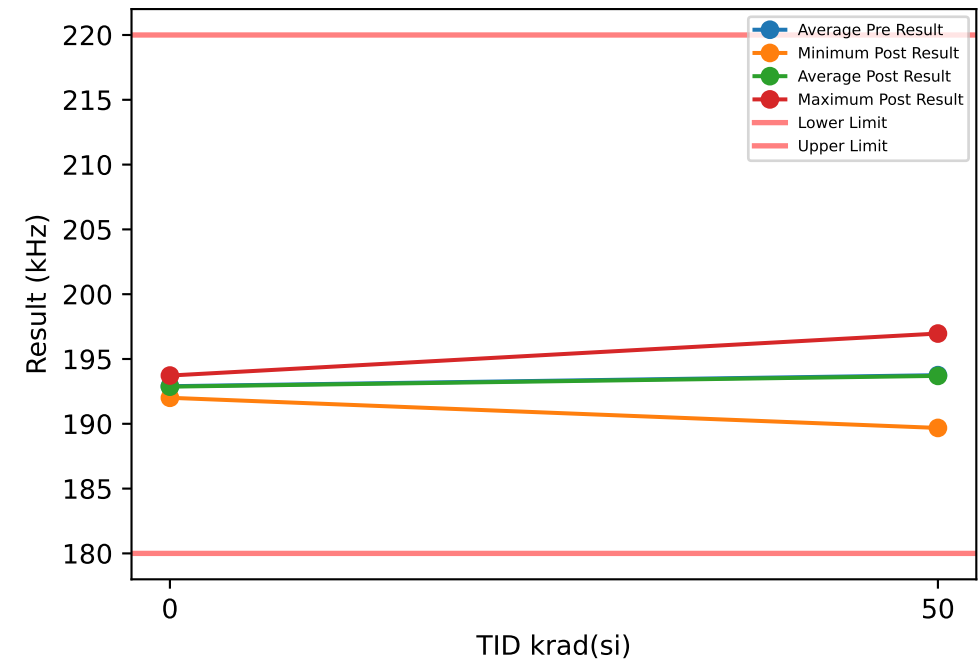


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	192.56	193.39	194.22	1.1743	192.51	193.36	194.21	1.1989	-0.0432	-0.0258	-0.0084	0.024607
50	190.28	194.24	197.67	2.2007	190.11	194.16	197.41	2.1641	-1.3864	-0.07893	0.8496	0.70129

Device Test: 20.33 FSW_EXT_RT_B(LEVEL|FREQ/RT/5/5/0/0/5/200kHz//@FSW_EXT_RT_B)

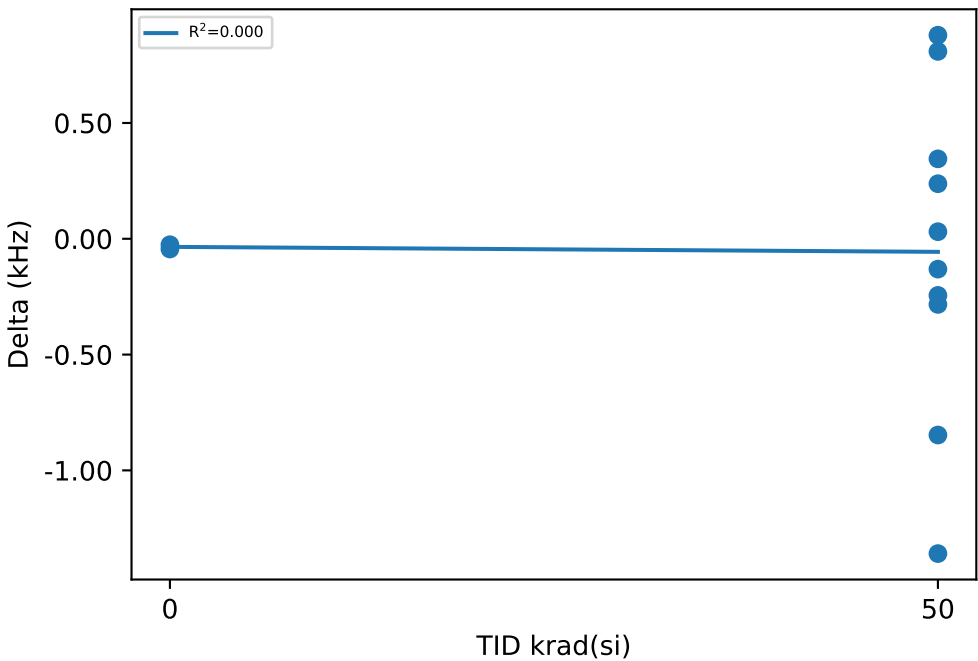
TID vs Result Stats



Test Results (Lower Limit = 180.0, Upper Limit = 220.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	192.05	192.01	-0.0442
2	0	Correlation	193.75	193.72	-0.0257
4	50	Bias	195.28	194.99	-0.2834
6	50	Bias	189.81	189.68	-0.131
7	50	Bias	194.38	194.41	0.0306
8	50	Bias	191.14	191.37	0.2377
9	50	Bias	193.72	194.53	0.809
11	50	Unbias	197.21	196.96	-0.2445
12	50	Unbias	195.4	195.75	0.3451
13	50	Unbias	193.53	192.17	-1.3593
14	50	Unbias	192.22	193.1	0.879
15	50	Unbias	194.84	193.99	-0.8473

TID vs Post - Pre Exposure Delta

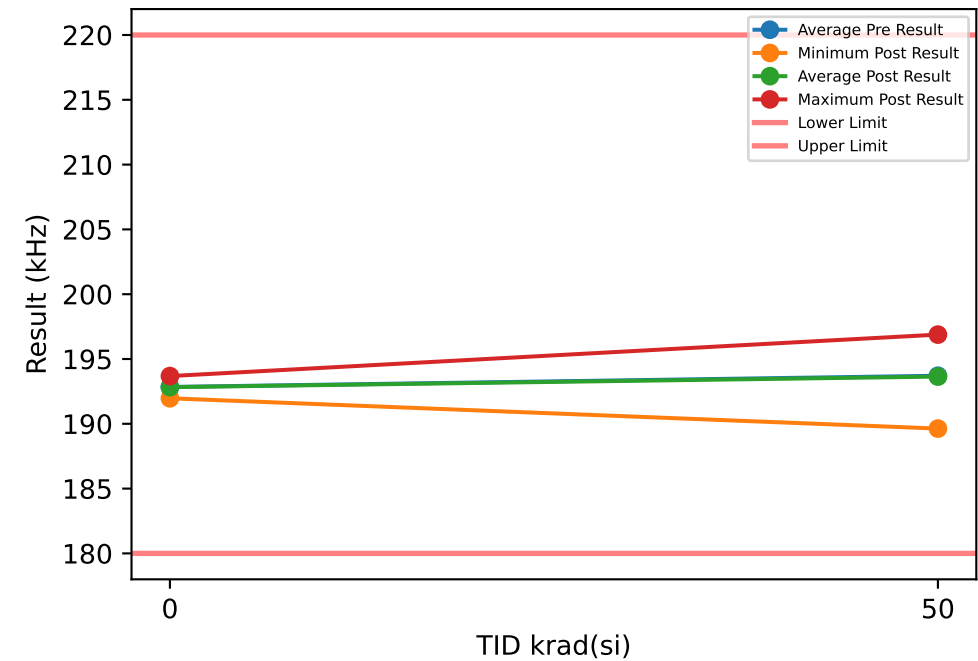


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	192.05	192.9	193.75	1.1999	192.01	192.87	193.72	1.213	-0.0442	-0.03495	-0.0257	0.013081
50	189.81	193.75	197.21	2.1943	189.68	193.7	196.96	2.1619	-1.3593	-0.05641	0.879	0.69079

Device Test: 20.35 FSW_EXT_RT_B(LEVEL|FREQ/RT/12/12/0/0/5/200kHz//@FSW_EXT_RT_B)

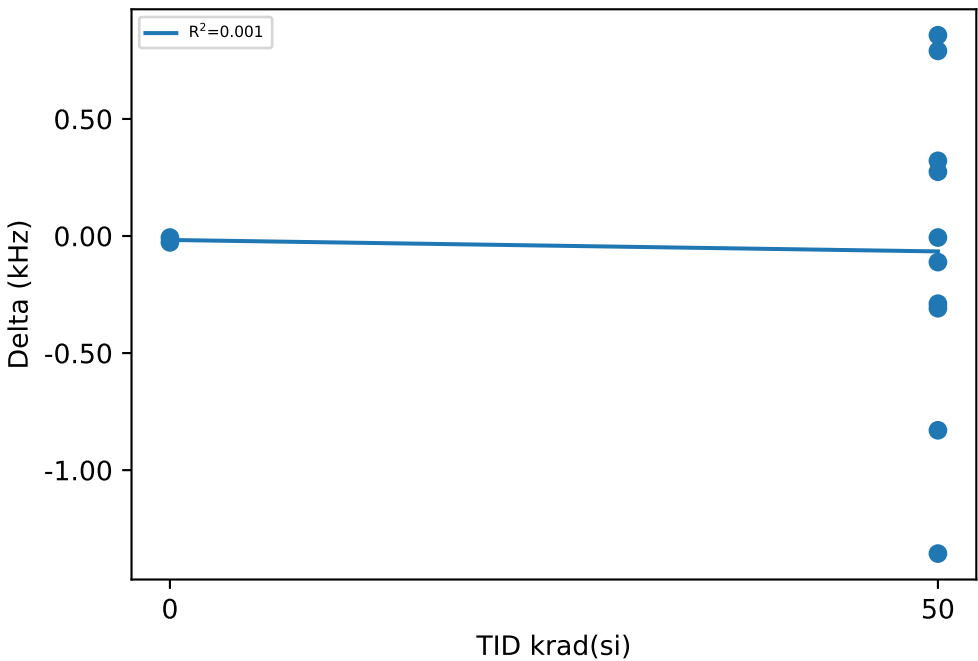
TID vs Result Stats



Test Results (Lower Limit = 180.0, Upper Limit = 220.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	192	191.97	-0.0273
2	0	Correlation	193.69	193.68	-0.0065
4	50	Bias	195.25	194.94	-0.3085
6	50	Bias	189.74	189.63	-0.1114
7	50	Bias	194.36	194.35	-0.0065
8	50	Bias	191.05	191.33	0.2746
9	50	Bias	193.66	194.45	0.7906
11	50	Unbias	197.17	196.88	-0.2891
12	50	Unbias	195.38	195.7	0.3212
13	50	Unbias	193.48	192.13	-1.3564
14	50	Unbias	192.17	193.03	0.8577
15	50	Unbias	194.8	193.97	-0.8298

TID vs Post - Pre Exposure Delta

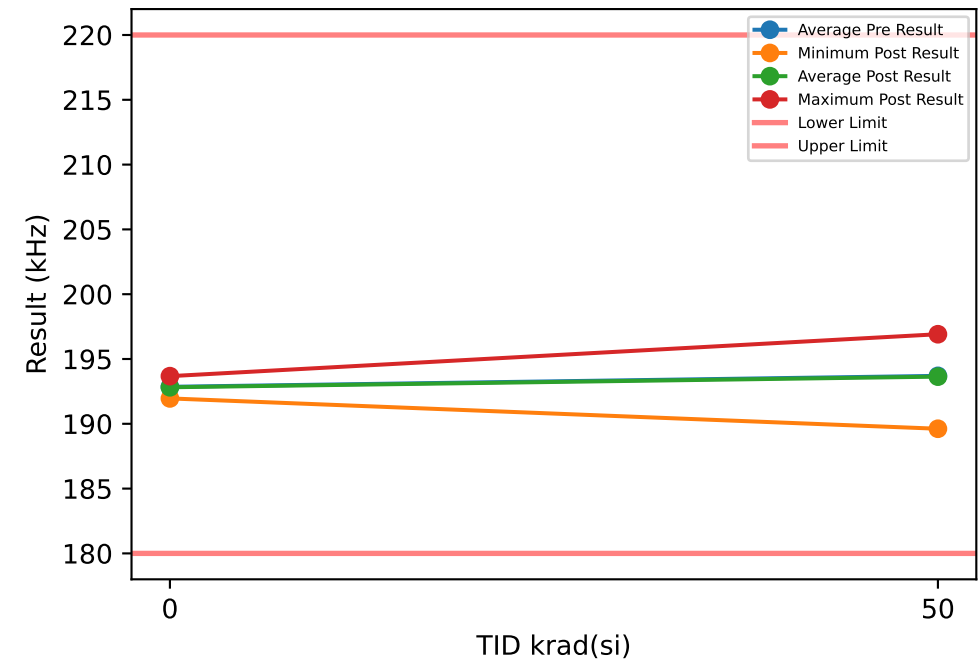


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	192	192.84	193.69	1.1964	191.97	192.83	193.68	1.2111	-0.0273	-0.0169	-0.0065	0.014708
50	189.74	193.71	197.17	2.2101	189.63	193.64	196.88	2.1553	-1.3564	-0.06576	0.8577	0.6844

Device Test: 20.37 FSW_EXT_RT_B(LEVEL|FREQ/RT/14/14/0/0/5/200kHz//@FSW_EXT_RT_B)

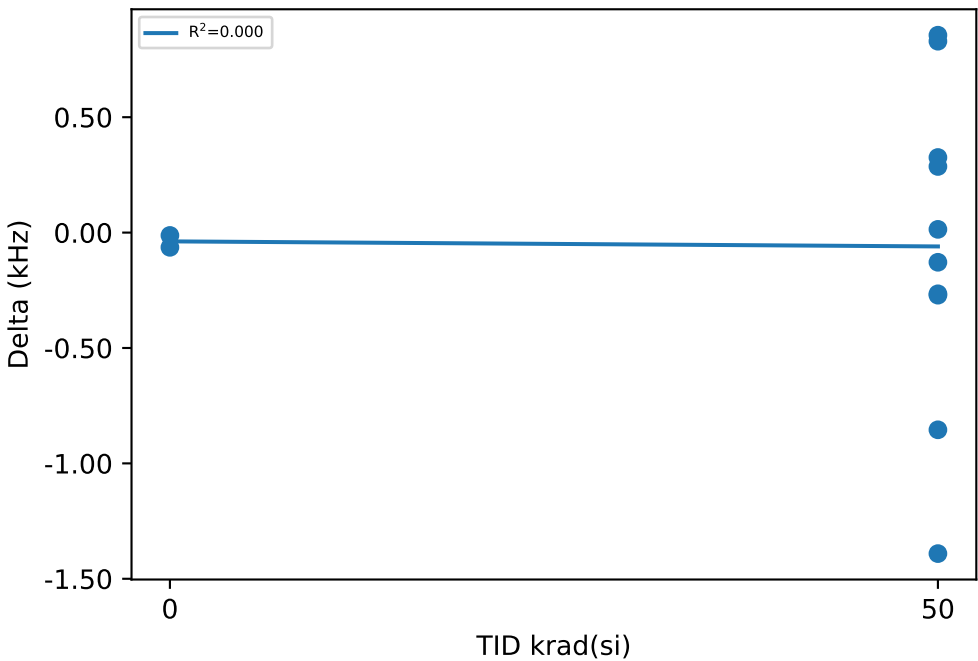
TID vs Result Stats



Test Results (Lower Limit = 180.0, Upper Limit = 220.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	192.02	191.96	-0.0638
2	0	Correlation	193.69	193.68	-0.0123
4	50	Bias	195.21	194.94	-0.2712
6	50	Bias	189.75	189.62	-0.1286
7	50	Bias	194.35	194.36	0.014
8	50	Bias	191.05	191.34	0.2865
9	50	Bias	193.64	194.47	0.8292
11	50	Unbias	197.18	196.91	-0.2652
12	50	Unbias	195.36	195.69	0.3254
13	50	Unbias	193.47	192.08	-1.3909
14	50	Unbias	192.19	193.05	0.8553
15	50	Unbias	194.78	193.92	-0.8545

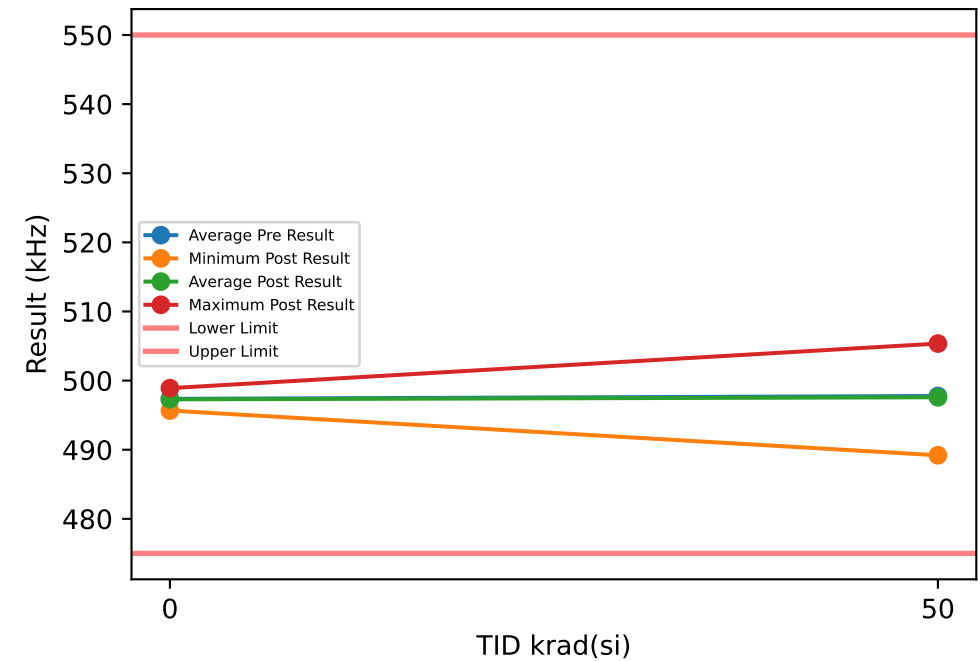
TID vs Post - Pre Exposure Delta



Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	192.02	192.86	193.69	1.178	191.96	192.82	193.68	1.2144	-0.0638	-0.03805	-0.0123	0.036416
50	189.75	193.7	197.18	2.2029	189.62	193.64	196.91	2.1633	-1.3909	-0.06	0.8553	0.69893

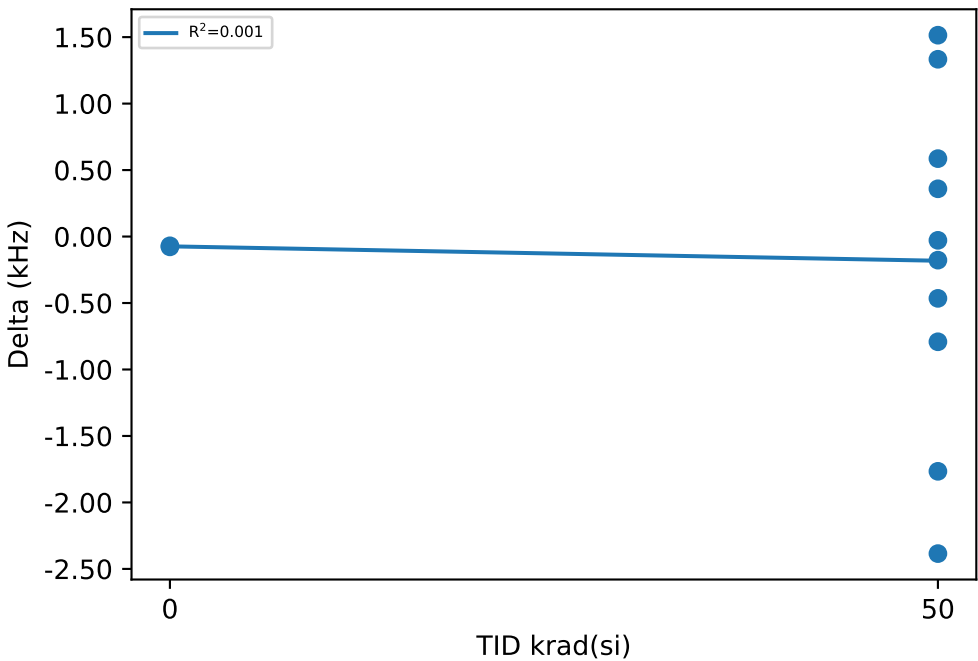
TID vs Result Stats



Test Results (Lower Limit = 475.0, Upper Limit = 550.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	495.74	495.67	-0.0697
2	0	Correlation	498.98	498.9	-0.0776
4	50	Bias	499.56	498.77	-0.7915
6	50	Bias	489.66	489.19	-0.465
7	50	Bias	498.26	498.23	-0.0285
8	50	Bias	492.02	492.61	0.5861
9	50	Bias	496.85	498.18	1.3335
11	50	Unbias	505.53	505.36	-0.1775
12	50	Unbias	502.06	502.41	0.3592
13	50	Unbias	499.05	496.66	-2.3848
14	50	Unbias	494.7	496.21	1.5145
15	50	Unbias	500.01	498.25	-1.7659

TID vs Post - Pre Exposure Delta

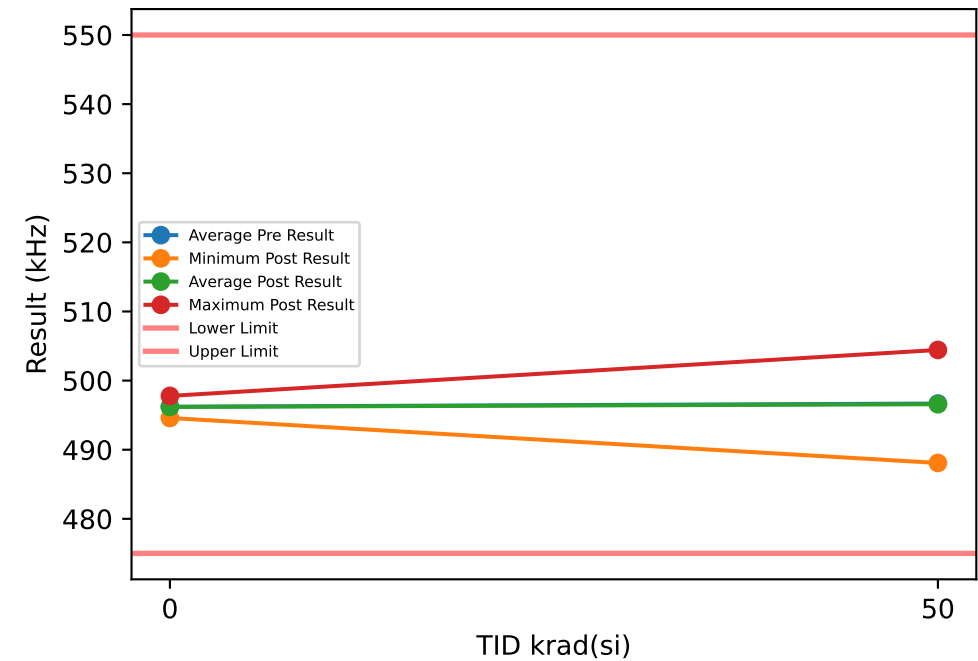


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	495.74	497.36	498.98	2.2943	495.67	497.29	498.9	2.2887	-0.0776	-0.07365	-0.0697	0.0055861
50	489.66	497.77	505.53	4.689	489.19	497.59	505.36	4.5247	-2.3848	-0.18199	1.5145	1.2425

Device Test: 20.43 FSW_EXT_RT_C(LEVEL|FREQ/RT/5/5/0/0/5/500kHz//@FSW_EXT_RT_C)

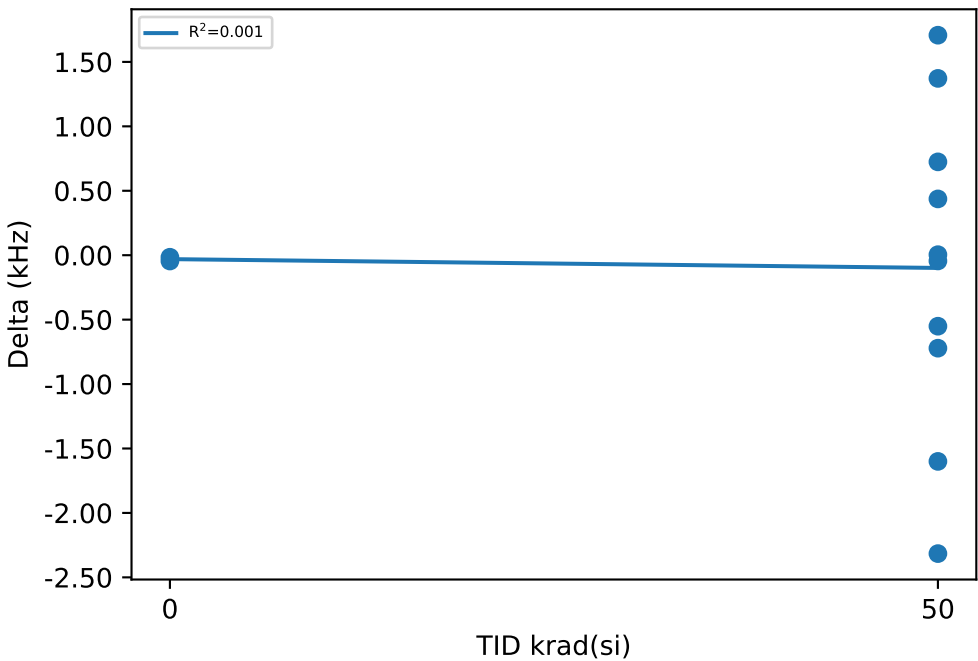
TID vs Result Stats



Test Results (Lower Limit = 475.0, Upper Limit = 550.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	494.61	494.59	-0.0158
2	0	Correlation	497.83	497.79	-0.0451
4	50	Bias	498.54	497.81	-0.7215
6	50	Bias	488.64	488.09	-0.551
7	50	Bias	497.1	497.1	0.0041
8	50	Bias	490.89	491.62	0.7243
9	50	Bias	495.84	497.21	1.3721
11	50	Unbias	504.48	504.43	-0.0446
12	50	Unbias	500.92	501.36	0.4368
13	50	Unbias	497.88	495.56	-2.3156
14	50	Unbias	493.64	495.34	1.7073
15	50	Unbias	498.88	497.28	-1.6001

TID vs Post - Pre Exposure Delta

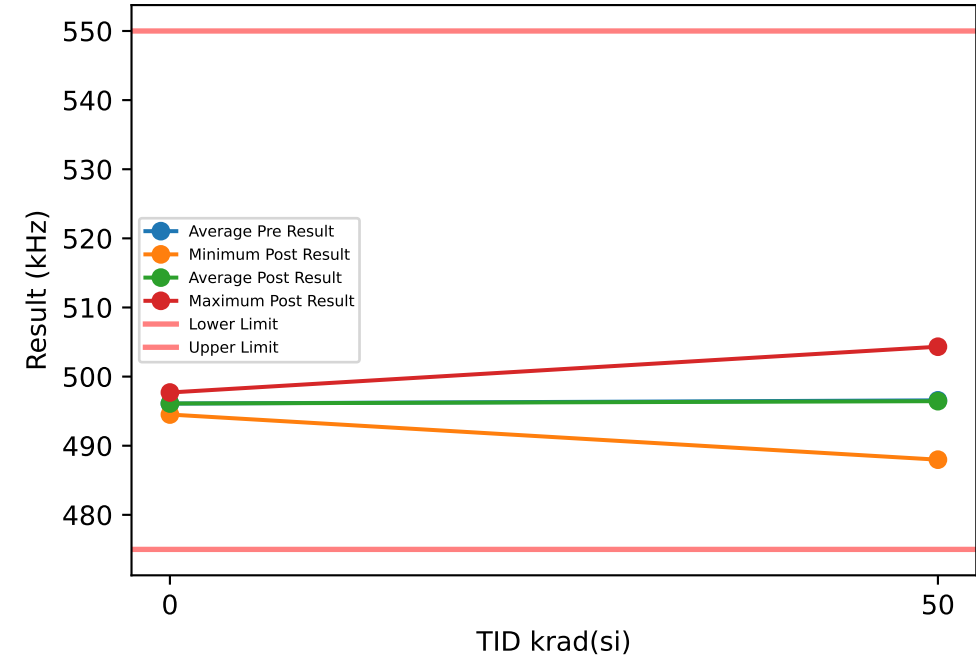


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	494.61	496.22	497.83	2.2797	494.59	496.19	497.79	2.259	-0.0451	-0.03045	-0.0158	0.020718
50	488.64	496.68	504.48	4.6771	488.09	496.58	504.43	4.553	-2.3156	-0.09882	1.7073	1.2545

Device Test: 20.47 FSW_EXT_RT_C(LEVEL|FREQ/RT/12/12/0/0/5/500kHz//@FSW_EXT_RT_C)

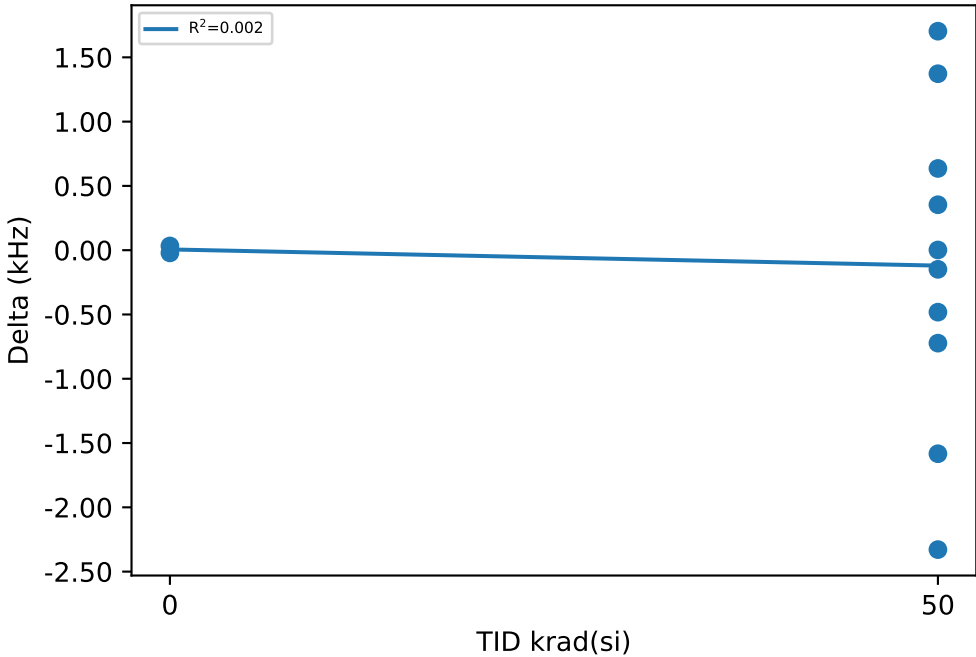
TID vs Result Stats



Test Results (Lower Limit = 475.0, Upper Limit = 550.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	494.48	494.51	0.0329
2	0	Correlation	497.72	497.7	-0.0211
4	50	Bias	498.4	497.67	-0.7231
6	50	Bias	488.46	487.98	-0.482
7	50	Bias	496.97	496.97	0.0017
8	50	Bias	490.84	491.47	0.6357
9	50	Bias	495.66	497.04	1.3725
11	50	Unbias	504.47	504.32	-0.1489
12	50	Unbias	500.84	501.2	0.3535
13	50	Unbias	497.7	495.38	-2.3288
14	50	Unbias	493.53	495.23	1.7033
15	50	Unbias	498.77	497.18	-1.5832

TID vs Post - Pre Exposure Delta

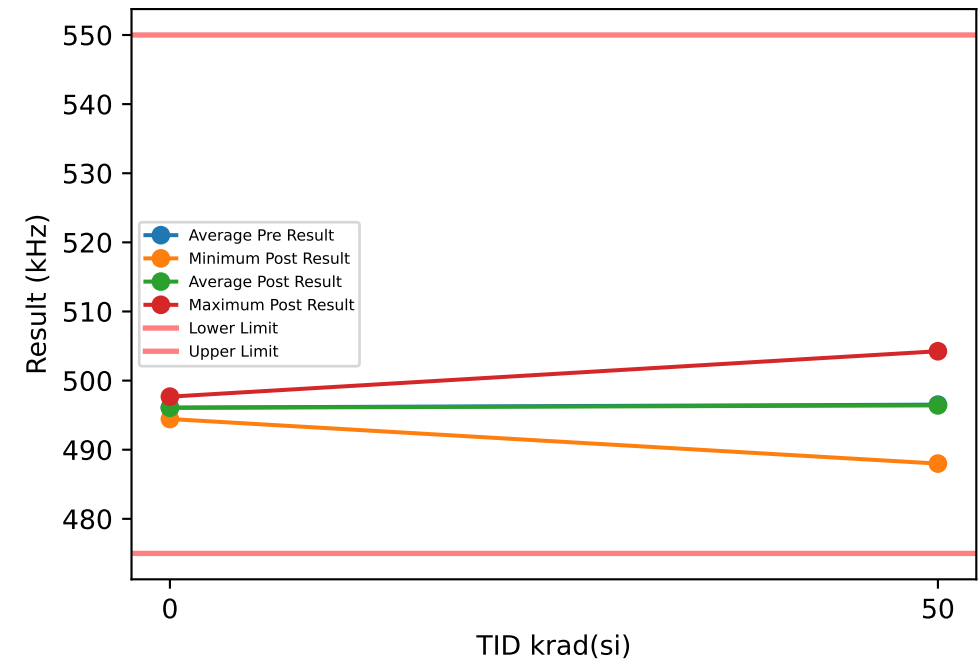


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	494.48	496.1	497.72	2.292	494.51	496.11	497.7	2.2538	-0.0211	0.0059	0.0329	0.038184
50	488.46	496.56	504.47	4.7024	487.98	496.44	504.32	4.5501	-2.3288	-0.11993	1.7033	1.2417

Device Test: 20.51 FSW_EXT_RT_C(LEVEL|FREQ/RT/14/14/0/0/5/500kHz//@FSW_EXT_RT_C)

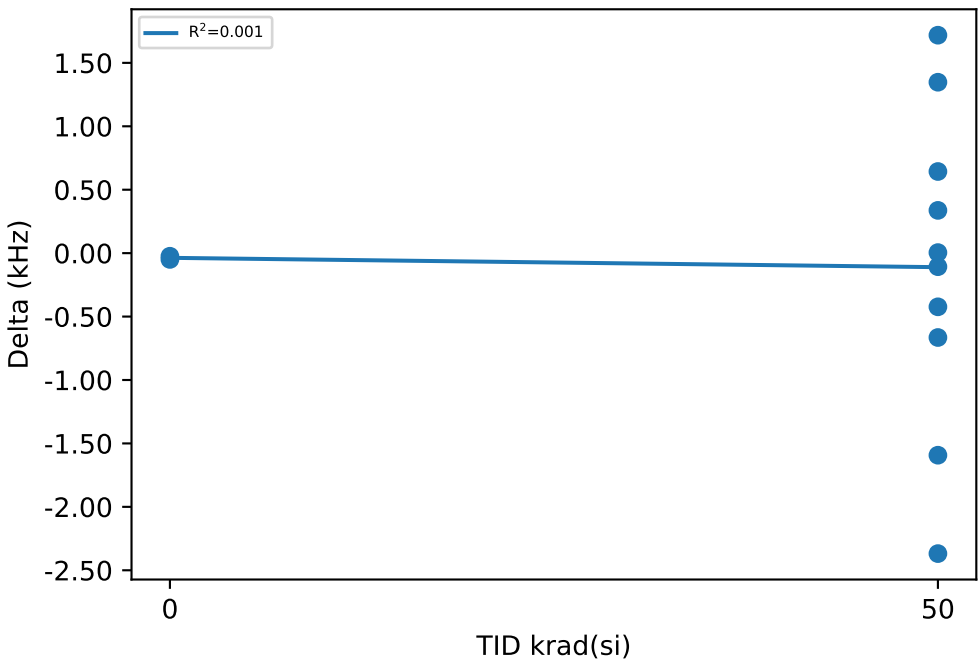
TID vs Result Stats



Test Results (Lower Limit = 475.0, Upper Limit = 550.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	494.47	494.44	-0.0244
2	0	Correlation	497.73	497.68	-0.0494
4	50	Bias	498.31	497.65	-0.665
6	50	Bias	488.42	487.99	-0.4231
7	50	Bias	496.93	496.94	0.0044
8	50	Bias	490.75	491.4	0.6436
9	50	Bias	495.69	497.04	1.3474
11	50	Unbias	504.35	504.25	-0.1068
12	50	Unbias	500.87	501.2	0.3371
13	50	Unbias	497.71	495.34	-2.3685
14	50	Unbias	493.49	495.21	1.7181
15	50	Unbias	498.71	497.12	-1.5929

TID vs Post - Pre Exposure Delta

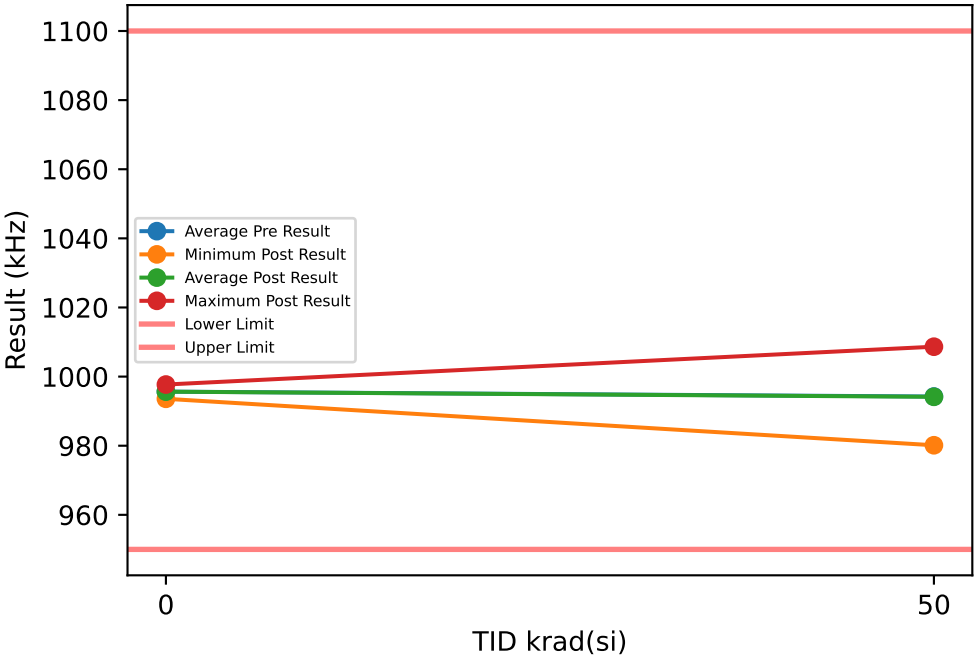


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	494.47	496.1	497.73	2.3056	494.44	496.06	497.68	2.2879	-0.0494	-0.0369	-0.0244	0.017678
50	488.42	496.52	504.35	4.698	487.99	496.41	504.25	4.5419	-2.3685	-0.11057	1.7181	1.2451

Device Test: 20.55 FSW_EXT_RT_D(LEVEL|FREQ/RT/4.5/4.5/0/0/4.5/1MHz//@FSW_EXT_RT_D)

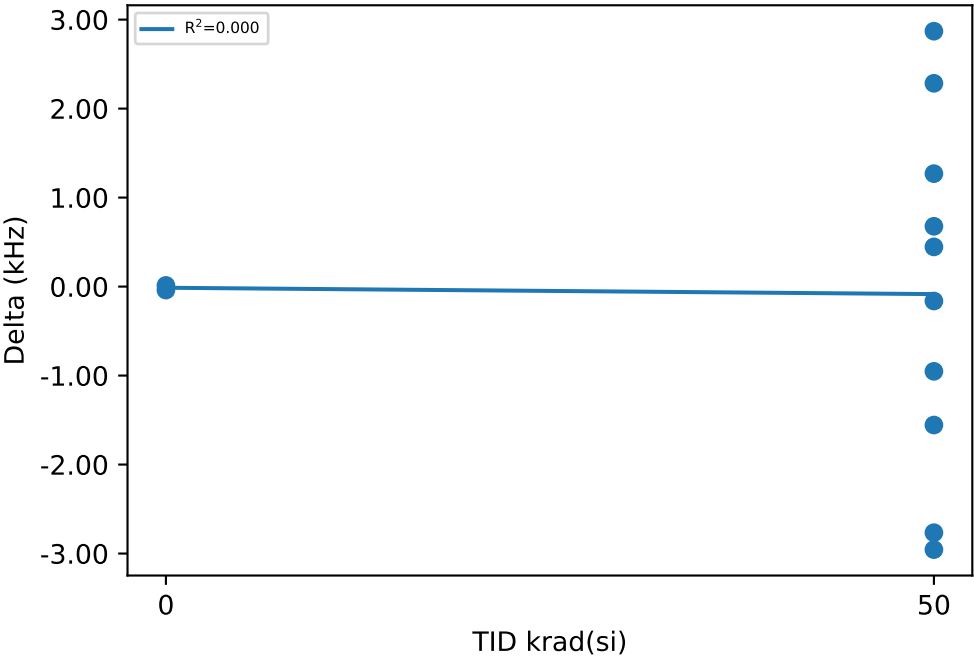
TID vs Result Stats



Test Results (Lower Limit = 950.0, Upper Limit = 1100.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	993.61	993.58	-0.0393
2	0	Correlation	997.69	997.7	0.013
4	50	Bias	996.35	994.8	-1.5558
6	50	Bias	981.09	980.13	-0.9524
7	50	Bias	994.61	994.45	-0.1622
8	50	Bias	983.71	984.98	1.2692
9	50	Bias	991.49	993.77	2.2842
11	50	Unbias	1008	1008.6	0.6775
12	50	Unbias	1002.1	1002.5	0.4459
13	50	Unbias	998.07	995.11	-2.9556
14	50	Unbias	988.59	991.46	2.8698
15	50	Unbias	998.42	995.66	-2.7657

TID vs Post - Pre Exposure Delta

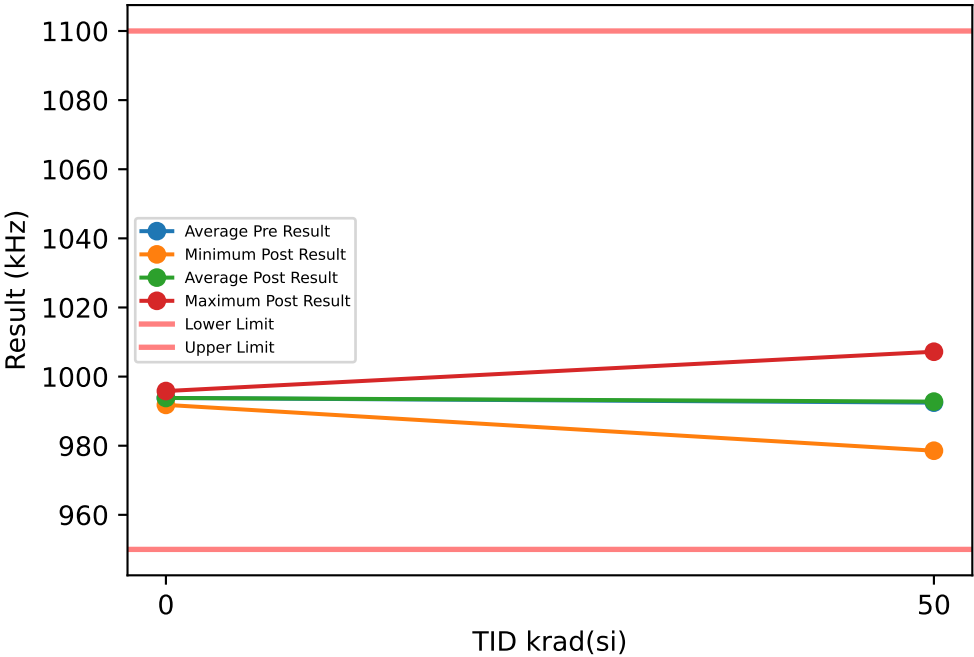


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	993.61	995.65	997.69	2.8815	993.58	995.64	997.7	2.9184	-0.0393	-0.01315	0.013	0.036982
50	981.09	994.24	1008	8.2315	980.13	994.15	1008.6	7.9695	-2.9556	-0.08451	2.8698	1.983

Device Test: 20.59 FSW_EXT_RT_D(LEVEL|FREQ/RT/5/5/0/0/5/1MHz//@FSW_EXT_RT_D)

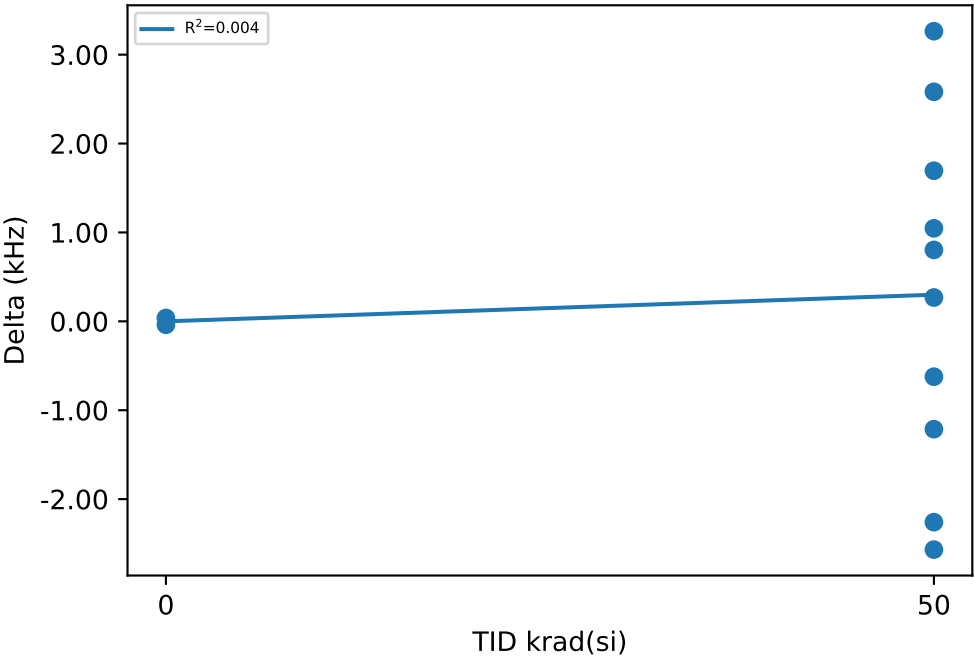
TID vs Result Stats



Test Results (Lower Limit = 950.0, Upper Limit = 1100.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	991.86	991.82	-0.0384
2	0	Correlation	995.78	995.82	0.0375
4	50	Bias	994.71	993.5	-1.2133
6	50	Bias	979.18	978.55	-0.623
7	50	Bias	992.72	992.99	0.2679
8	50	Bias	982.03	983.72	1.6944
9	50	Bias	989.79	992.37	2.582
11	50	Unbias	1006.1	1007.2	1.0462
12	50	Unbias	1000.4	1001.2	0.8034
13	50	Unbias	996.2	993.63	-2.568
14	50	Unbias	986.75	990.01	3.2639
15	50	Unbias	996.72	994.46	-2.2594

TID vs Post - Pre Exposure Delta

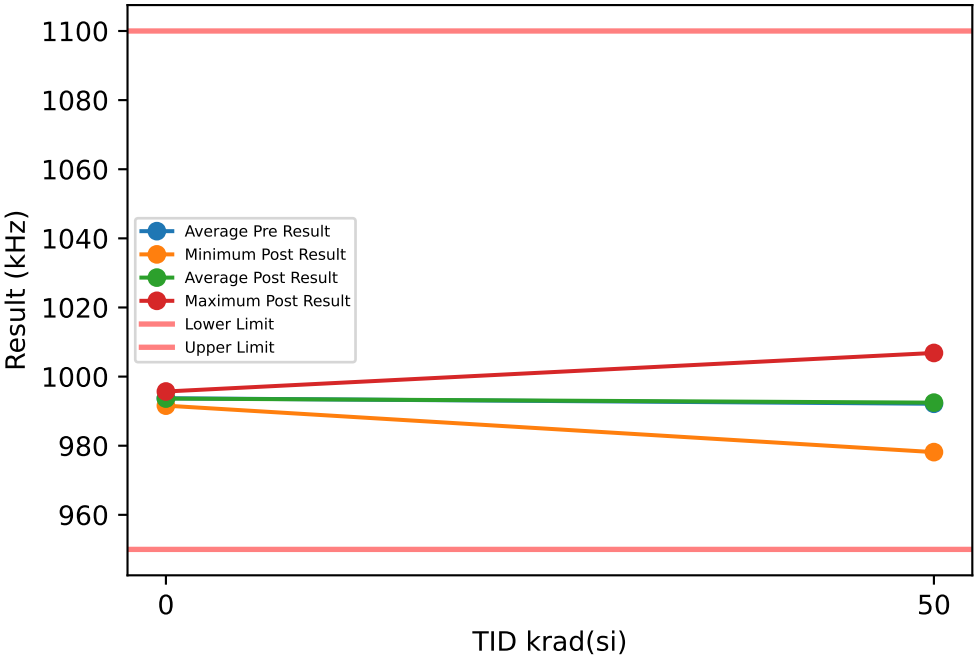


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	991.86	993.82	995.78	2.7772	991.82	993.82	995.82	2.8308	-0.0384	-0.00045	0.0375	0.053669
50	979.18	992.46	1006.1	8.2498	978.55	992.76	1007.2	7.9922	-2.568	0.29941	3.2639	1.9626

Device Test: 20.63 FSW_EXT_RT_D(LEVEL|FREQ/RT/12/12/0/0/5/1MHz//@FSW_EXT_RT_D)

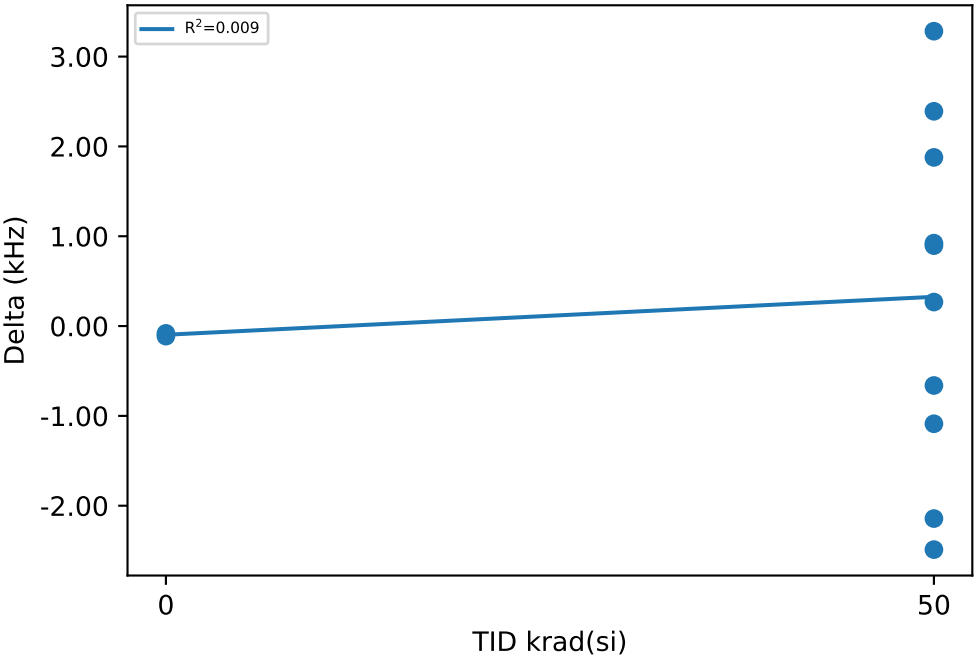
TID vs Result Stats



Test Results (Lower Limit = 950.0, Upper Limit = 1100.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	991.68	991.6	-0.0815
2	0	Correlation	995.8	995.69	-0.1123
4	50	Bias	994.37	993.28	-1.0877
6	50	Bias	978.81	978.15	-0.6616
7	50	Bias	992.22	992.48	0.2674
8	50	Bias	981.67	983.55	1.8776
9	50	Bias	989.5	991.89	2.3909
11	50	Unbias	1005.9	1006.8	0.8954
12	50	Unbias	999.96	1000.9	0.923
13	50	Unbias	995.92	993.43	-2.4886
14	50	Unbias	986.59	989.87	3.2827
15	50	Unbias	996.4	994.26	-2.1431

TID vs Post - Pre Exposure Delta

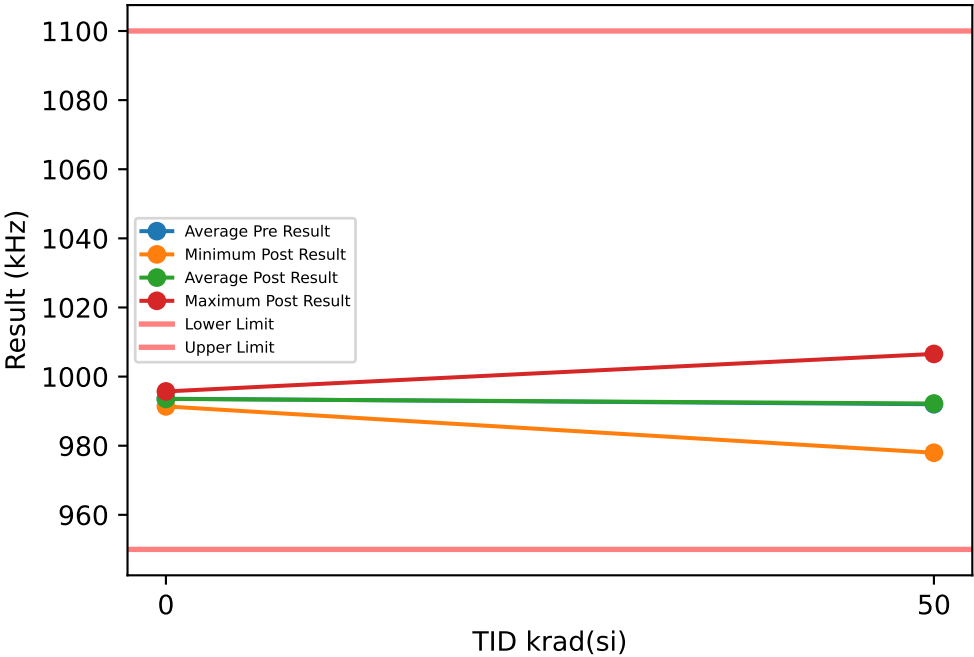


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	991.68	993.74	995.8	2.915	991.6	993.64	995.69	2.8932	-0.1123	-0.0969	-0.0815	0.021779
50	978.81	992.14	1005.9	8.2624	978.15	992.46	1006.8	7.986	-2.4886	0.3256	3.2827	1.9175

Device Test: 20.67 FSW_EXT_RT_D(LEVEL|FREQ/RT/14/14/0/0/5/1MHz//@FSW_EXT_RT_D)

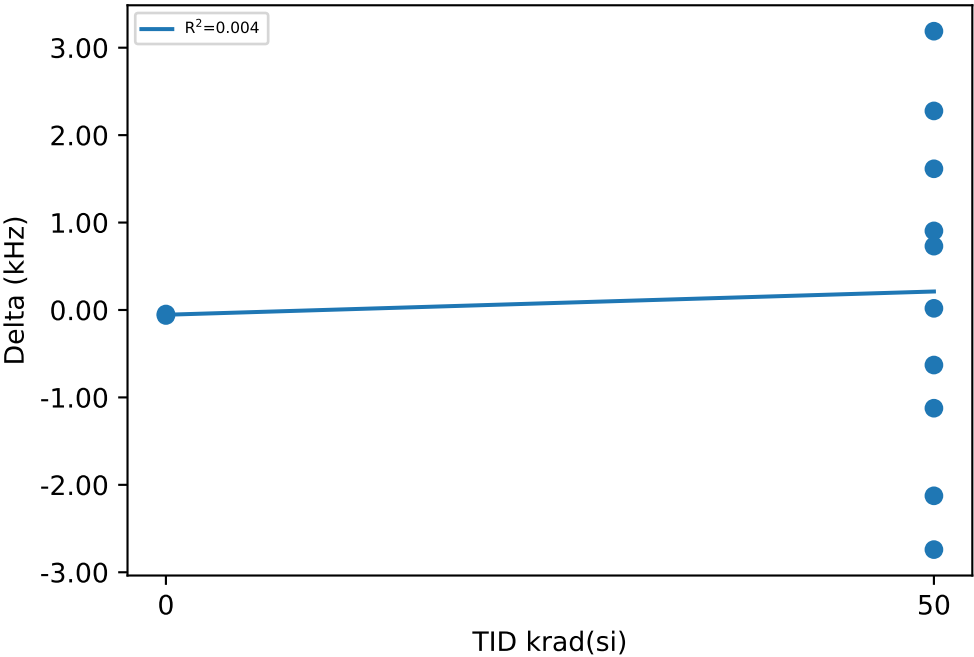
TID vs Result Stats



Test Results (Lower Limit = 950.0, Upper Limit = 1100.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	991.44	991.37	-0.0629
2	0	Correlation	995.75	995.71	-0.0462
4	50	Bias	994.11	992.99	-1.1235
6	50	Bias	978.6	977.97	-0.6297
7	50	Bias	992.2	992.22	0.019
8	50	Bias	981.6	983.22	1.615
9	50	Bias	989.34	991.62	2.2769
11	50	Unbias	1005.8	1006.6	0.7301
12	50	Unbias	999.68	1000.6	0.9046
13	50	Unbias	995.93	993.19	-2.7407
14	50	Unbias	986.58	989.77	3.1888
15	50	Unbias	996.12	994	-2.1255

TID vs Post - Pre Exposure Delta

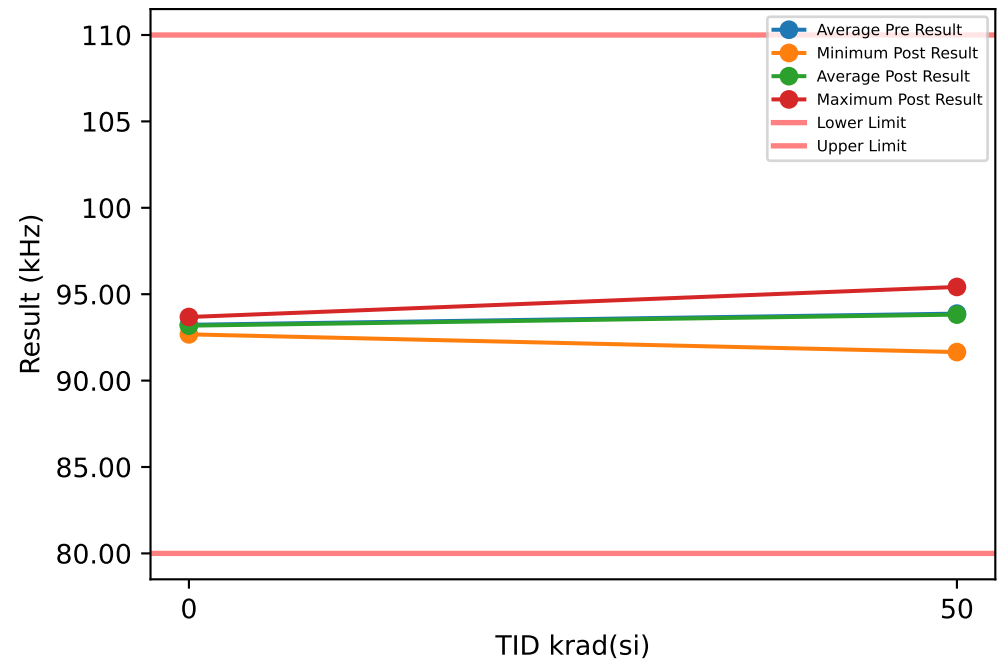


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	991.44	993.6	995.75	3.0531	991.37	993.54	995.71	3.0649	-0.0629	-0.05455	-0.0462	0.011809
50	978.6	992	1005.8	8.2417	977.97	992.21	1006.6	7.964	-2.7407	0.2115	3.1888	1.9018

Device Test: 20.71 FSW_EXT_RT_A(LEVEL|FREQ/RT/4.5/4.5/0/1000/4.5/100kHz//@FSW_EXT_RT_A)

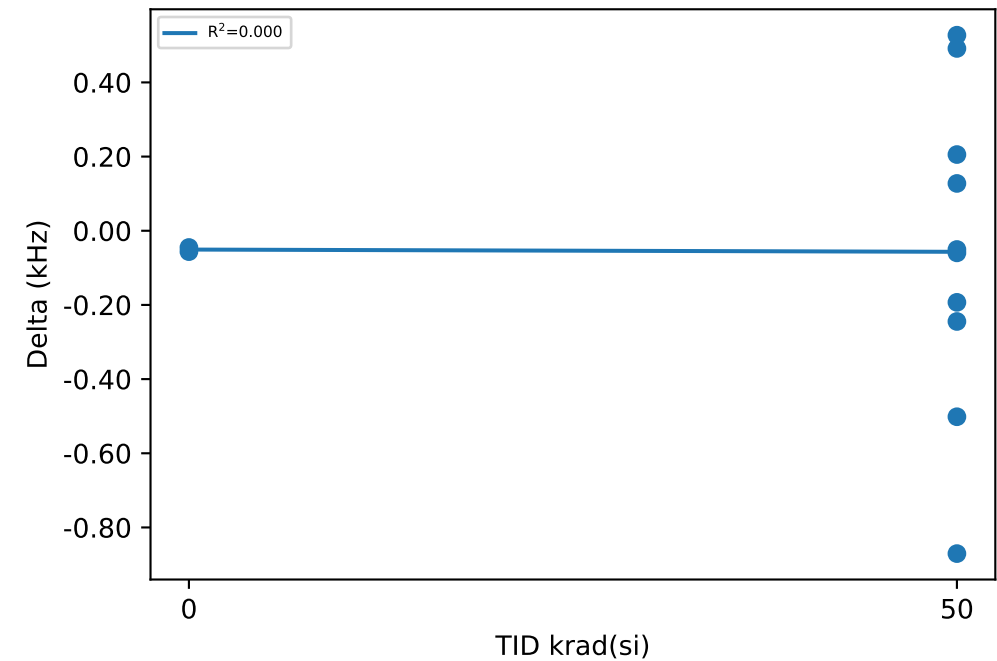
TID vs Result Stats



Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	92.722	92.677	-0.0451
2	0	Correlation	93.736	93.68	-0.0563
4	50	Bias	95.003	94.81	-0.193
6	50	Bias	91.71	91.65	-0.0596
7	50	Bias	94.519	94.468	-0.0505
8	50	Bias	92.35	92.478	0.1276
9	50	Bias	93.98	94.507	0.5273
11	50	Unbias	95.664	95.419	-0.2446
12	50	Unbias	94.626	94.832	0.2055
13	50	Unbias	93.41	92.54	-0.8705
14	50	Unbias	92.973	93.464	0.4916
15	50	Unbias	94.524	94.022	-0.5015

TID vs Post - Pre Exposure Delta

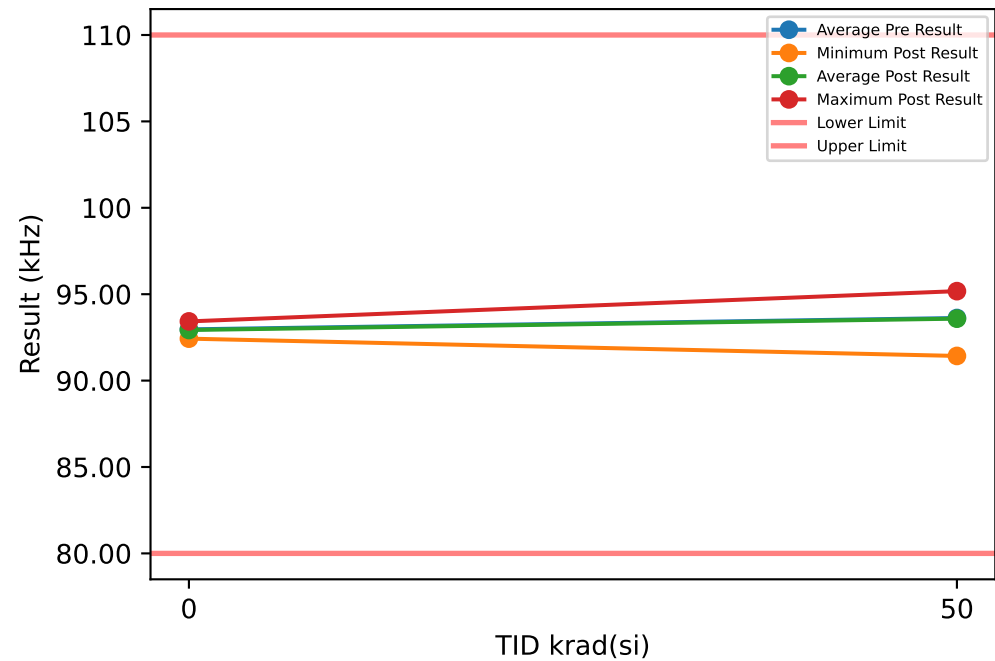


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	92.722	93.229	93.736	0.71736	92.677	93.178	93.68	0.70944	-0.0563	-0.0507	-0.0451	0.0079196
50	91.71	93.876	95.664	1.2439	91.65	93.819	95.419	1.2369	-0.8705	-0.05677	0.5273	0.42927

Device Test: 20.73 FSW_EXT_RT_A(LEVEL|FREQ/RT/5/5/0/1000/5/100kHz//@FSW_EXT_RT_A)

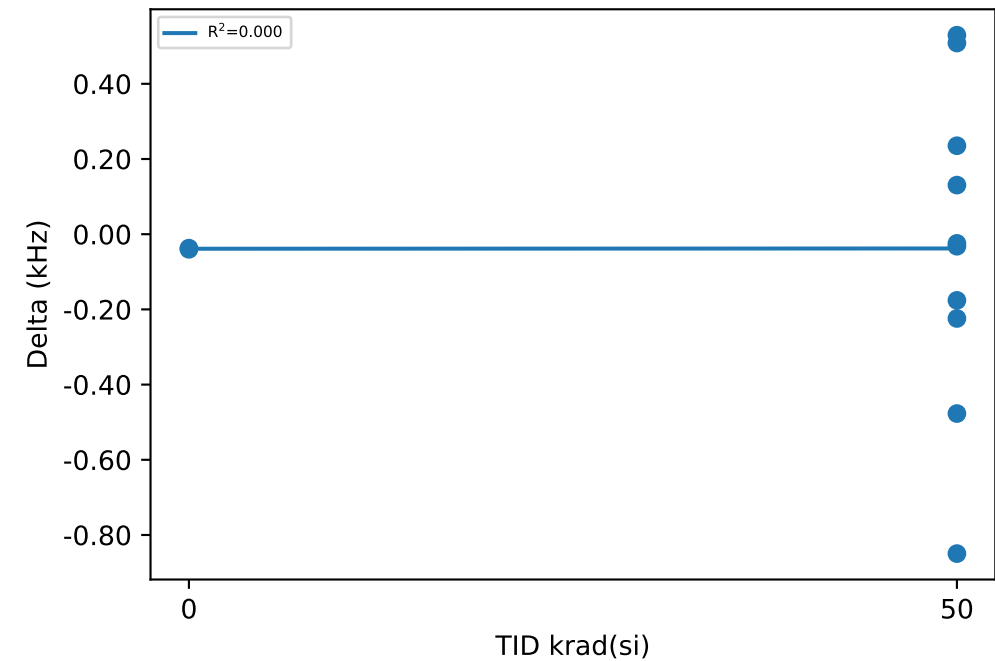
TID vs Result Stats



Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	92.465	92.428	-0.0371
2	0	Correlation	93.466	93.425	-0.0402
4	50	Bias	94.763	94.587	-0.176
6	50	Bias	91.451	91.427	-0.0244
7	50	Bias	94.256	94.224	-0.032
8	50	Bias	92.1	92.231	0.1306
9	50	Bias	93.743	94.272	0.5293
11	50	Unbias	95.401	95.176	-0.2241
12	50	Unbias	94.355	94.59	0.2353
13	50	Unbias	93.155	92.306	-0.8495
14	50	Unbias	92.726	93.234	0.5085
15	50	Unbias	94.267	93.79	-0.477

TID vs Post - Pre Exposure Delta

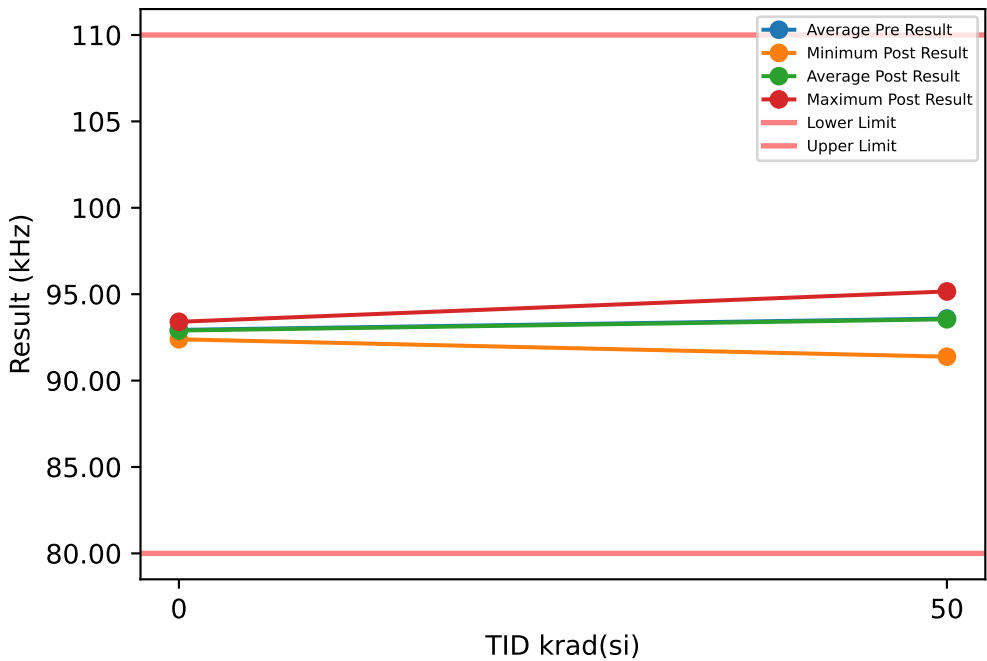


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	92.465	92.965	93.466	0.70753	92.428	92.927	93.425	0.70534	-0.0402	-0.03865	-0.0371	0.002192
50	91.451	93.622	95.401	1.242	91.427	93.584	95.176	1.2347	-0.8495	-0.03793	0.5293	0.42541

Device Test: 20.75 FSW_EXT_RT_A(LEVEL|FREQ/RT/12/12/0/1000/5/100kHz//@FSW_EXT_RT_A)

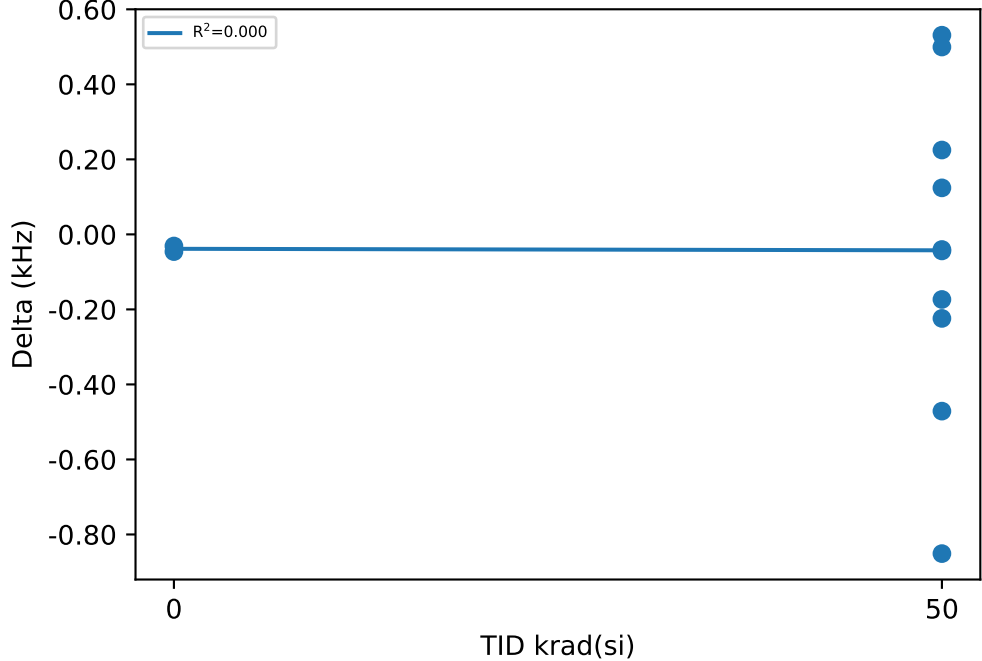
TID vs Result Stats



Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	92.436	92.39	-0.0459
2	0	Correlation	93.434	93.403	-0.031
4	50	Bias	94.727	94.554	-0.1735
6	50	Bias	91.429	91.385	-0.0441
7	50	Bias	94.224	94.184	-0.0403
8	50	Bias	92.071	92.195	0.124
9	50	Bias	93.698	94.229	0.531
11	50	Unbias	95.383	95.159	-0.224
12	50	Unbias	94.325	94.55	0.2249
13	50	Unbias	93.116	92.265	-0.851
14	50	Unbias	92.705	93.205	0.4995
15	50	Unbias	94.223	93.752	-0.4712

TID vs Post - Pre Exposure Delta

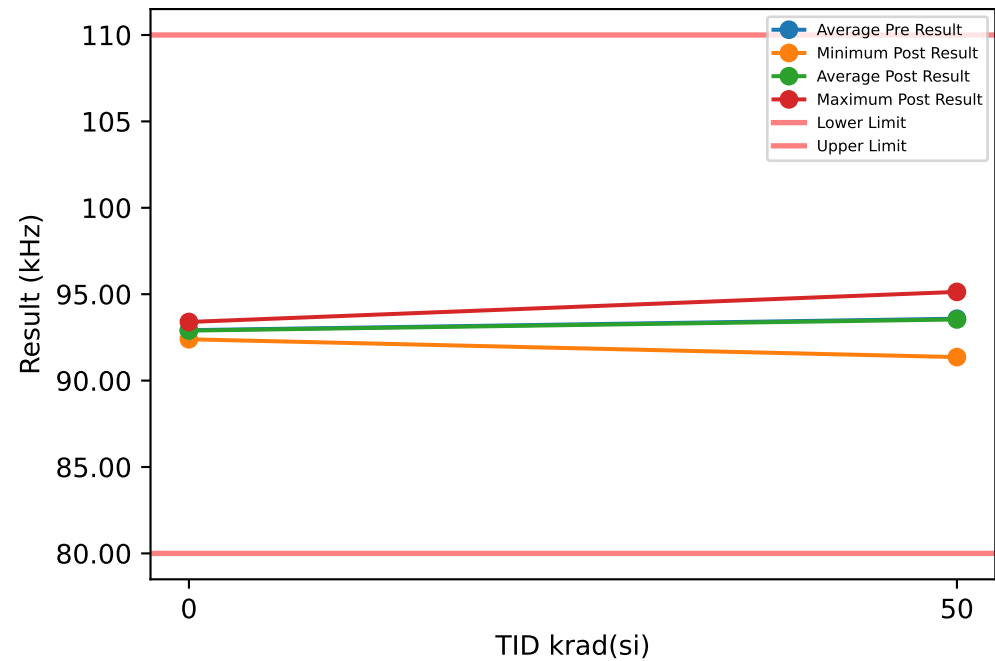


Test Statistics (kHz)

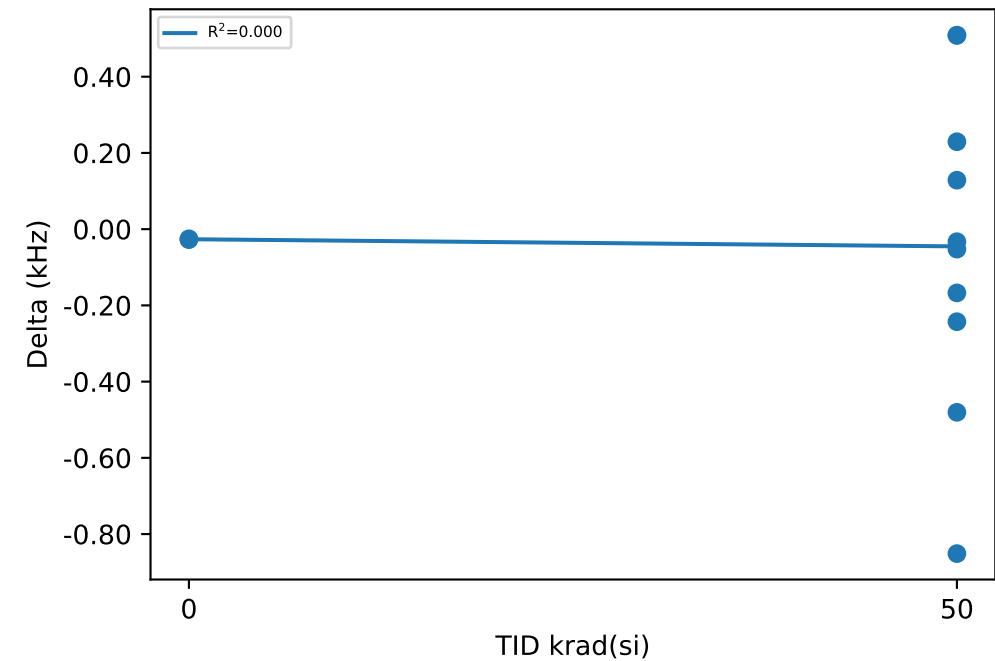
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	92.436	92.935	93.434	0.70562	92.39	92.896	93.403	0.71616	-0.0459	-0.03845	-0.031	0.010536
50	91.429	93.59	95.383	1.2404	91.385	93.548	95.159	1.238	-0.851	-0.04247	0.531	0.42288

Device Test: 20.77 FSW_EXT_RT_A(LEVEL|FREQ/RT/14/14/0/1000/5/100kHz//@FSW_EXT_RT_A)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

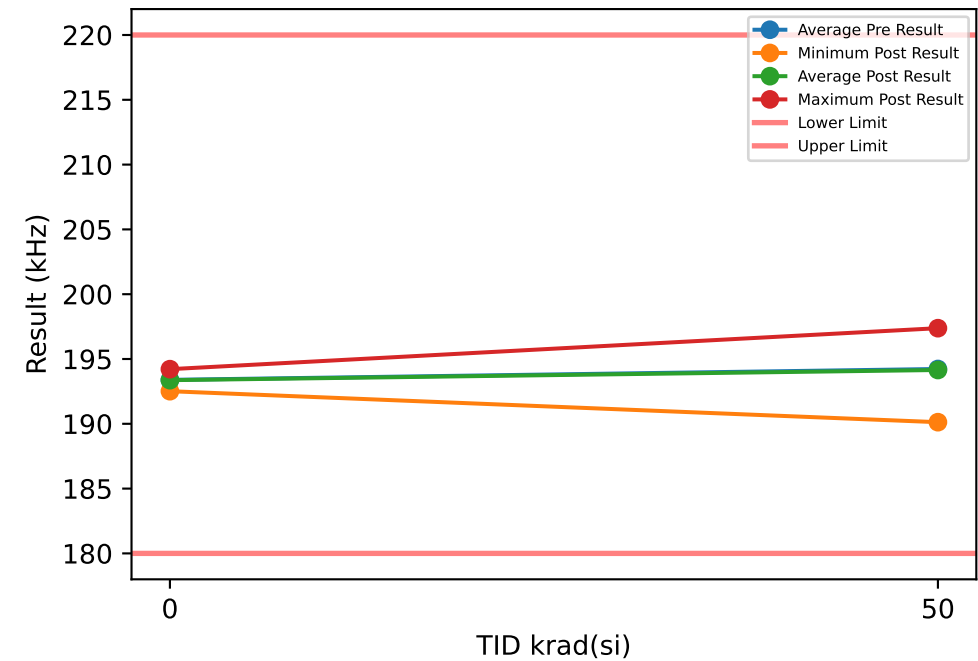
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	92.416	92.391	-0.0253
2	0	Correlation	93.42	93.393	-0.0275
4	50	Bias	94.719	94.552	-0.1672
6	50	Bias	91.412	91.36	-0.0524
7	50	Bias	94.213	94.18	-0.0329
8	50	Bias	92.061	92.189	0.1285
9	50	Bias	93.702	94.21	0.5085
11	50	Unbias	95.376	95.133	-0.2428
12	50	Unbias	94.321	94.55	0.2294
13	50	Unbias	93.107	92.256	-0.8512
14	50	Unbias	92.699	93.208	0.5089
15	50	Unbias	94.211	93.73	-0.4805

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	92.416	92.918	93.42	0.70979	92.391	92.892	93.393	0.70824	-0.0275	-0.0264	-0.0253	0.0015556
50	91.412	93.582	95.376	1.2424	91.36	93.537	95.133	1.2389	-0.8512	-0.04517	0.5089	0.42327

Device Test: 20.79 FSW_EXT_RT_B(LEVEL|FREQ/RT/4.5/4.5/0/1000/4.5/200kHz//@FSW_EXT_RT_B)

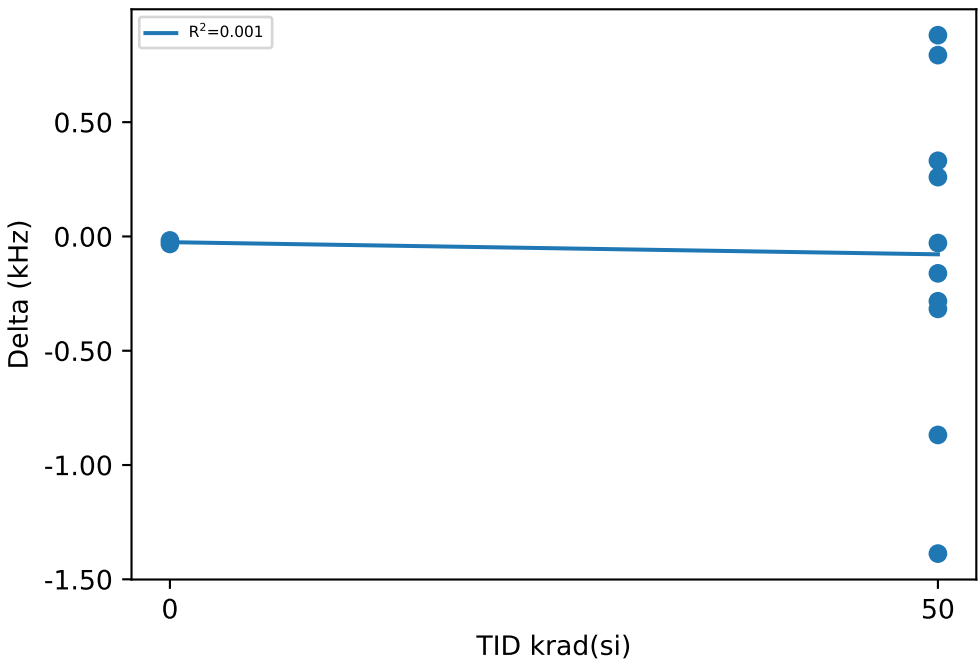
TID vs Result Stats



Test Results (Lower Limit = 180.0, Upper Limit = 220.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	192.55	192.52	-0.0327
2	0	Correlation	194.23	194.22	-0.0173
4	50	Bias	195.74	195.42	-0.3169
6	50	Bias	190.29	190.12	-0.1614
7	50	Bias	194.89	194.86	-0.0288
8	50	Bias	191.59	191.85	0.2596
9	50	Bias	194.18	194.97	0.7933
11	50	Unbias	197.66	197.38	-0.2834
12	50	Unbias	195.91	196.24	0.331
13	50	Unbias	194.02	192.63	-1.3875
14	50	Unbias	192.68	193.56	0.8805
15	50	Unbias	195.34	194.47	-0.8684

TID vs Post - Pre Exposure Delta

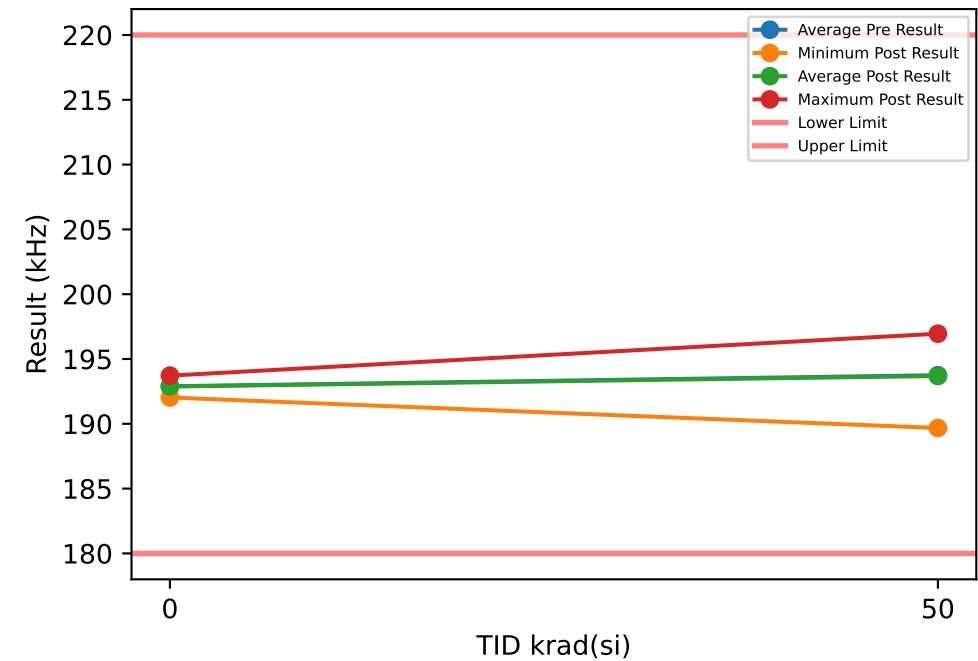


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	192.55	193.39	194.23	1.191	192.52	193.37	194.22	1.2019	-0.0327	-0.025	-0.0173	0.010889
50	190.29	194.23	197.66	2.1976	190.12	194.15	197.38	2.155	-1.3875	-0.0782	0.8805	0.69979

Device Test: 20.81 FSW_EXT_RT_B(LEVEL|FREQ/RT/5/5/0/1000/5/200kHz//@FSW_EXT_RT_B)

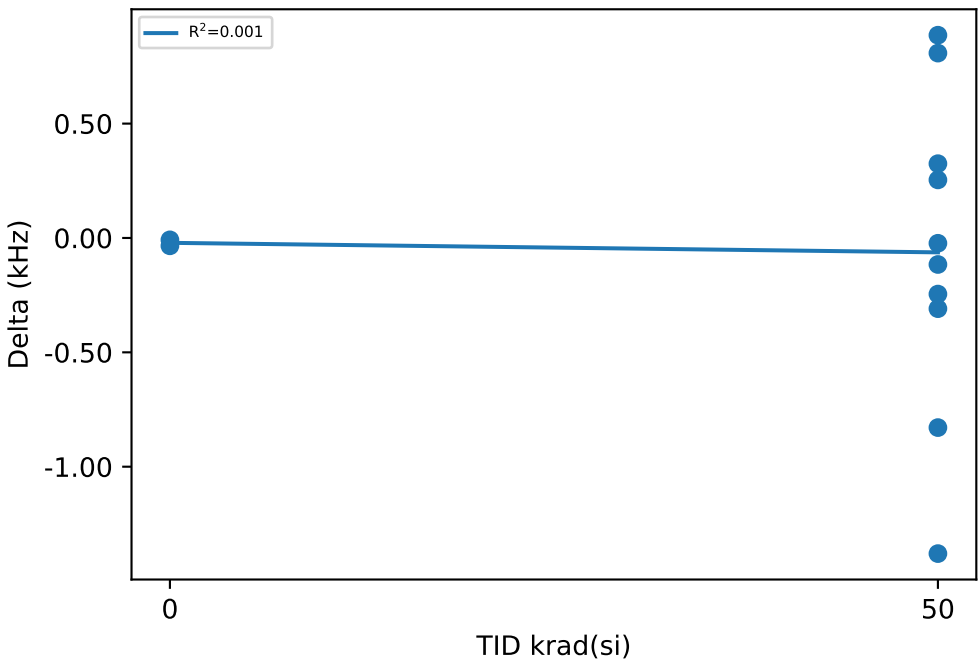
TID vs Result Stats



Test Results (Lower Limit = 180.0, Upper Limit = 220.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	192.04	192.03	-0.0082
2	0	Correlation	193.75	193.72	-0.0343
4	50	Bias	195.28	194.97	-0.3091
6	50	Bias	189.79	189.68	-0.1159
7	50	Bias	194.42	194.4	-0.0232
8	50	Bias	191.13	191.38	0.2539
9	50	Bias	193.7	194.51	0.8082
11	50	Unbias	197.2	196.95	-0.2453
12	50	Unbias	195.41	195.74	0.3248
13	50	Unbias	193.52	192.14	-1.3799
14	50	Unbias	192.22	193.1	0.8865
15	50	Unbias	194.82	194	-0.829

TID vs Post - Pre Exposure Delta

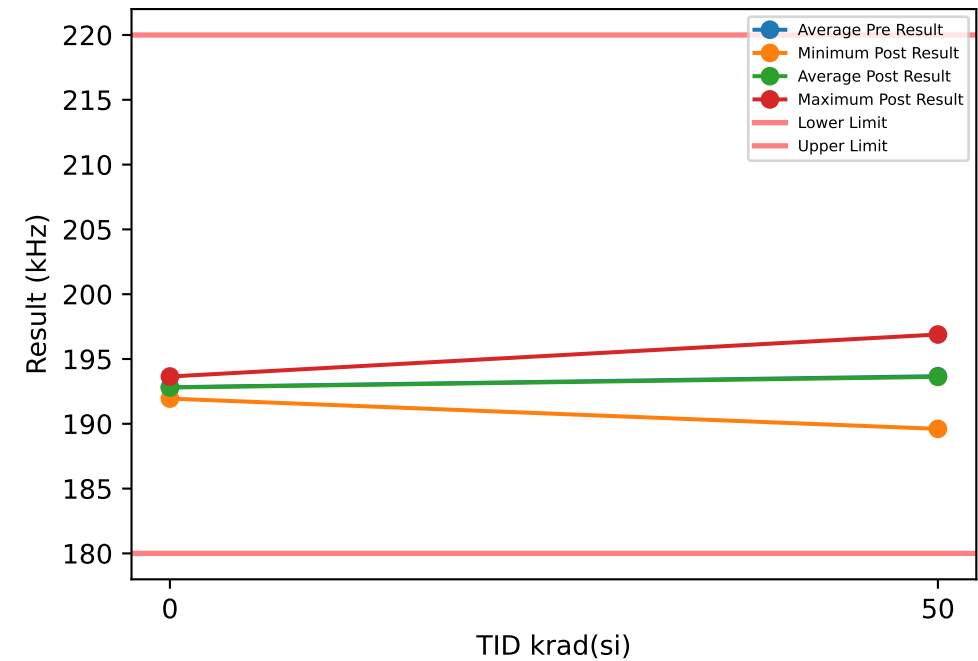


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	192.04	192.89	193.75	1.2106	192.03	192.87	193.72	1.1922	-0.0343	-0.02125	-0.0082	0.018455
50	189.79	193.75	197.2	2.1995	189.68	193.69	196.95	2.1583	-1.3799	-0.0629	0.8865	0.69366

Device Test: 20.83 FSW_EXT_RT_B(LEVEL|FREQ/RT/12/12/0/1000/5/200kHz//@FSW_EXT_RT_B)

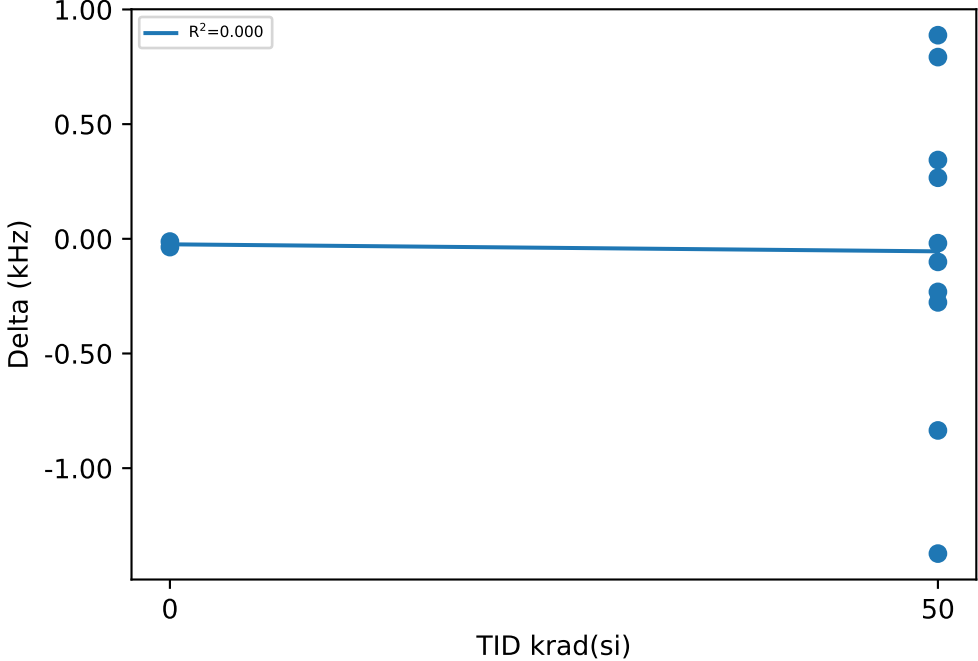
TID vs Result Stats



Test Results (Lower Limit = 180.0, Upper Limit = 220.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	191.98	191.95	-0.0361
2	0	Correlation	193.66	193.65	-0.0119
4	50	Bias	195.2	194.92	-0.2772
6	50	Bias	189.71	189.61	-0.1006
7	50	Bias	194.32	194.3	-0.019
8	50	Bias	191.04	191.3	0.2662
9	50	Bias	193.66	194.45	0.7923
11	50	Unbias	197.12	196.89	-0.2314
12	50	Unbias	195.35	195.69	0.3435
13	50	Unbias	193.45	192.08	-1.3725
14	50	Unbias	192.15	193.04	0.8878
15	50	Unbias	194.75	193.91	-0.8355

TID vs Post - Pre Exposure Delta

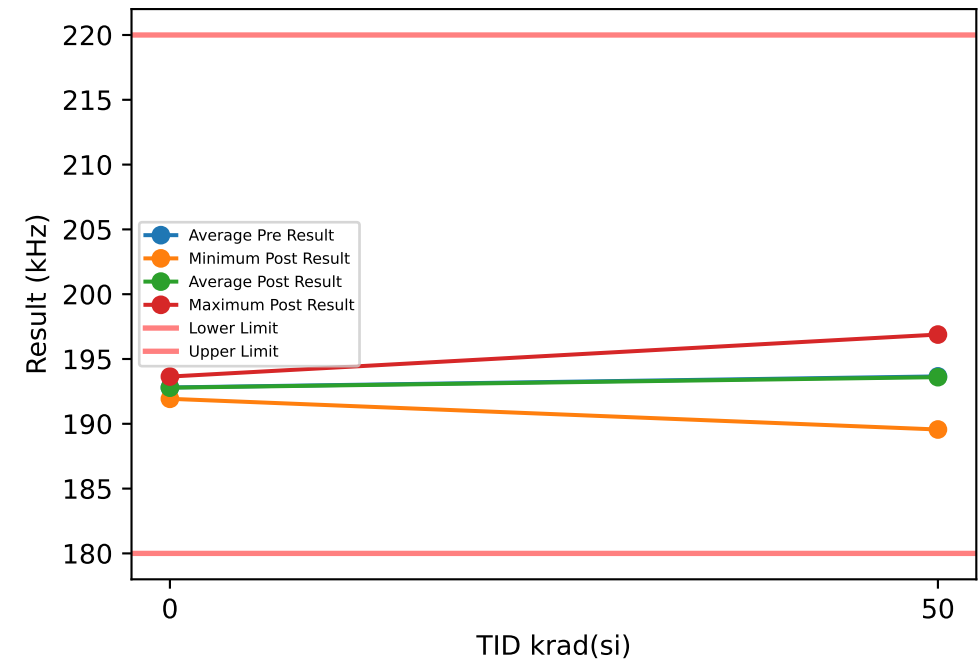


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	191.98	192.82	193.66	1.1873	191.95	192.8	193.65	1.2044	-0.0361	-0.024	-0.0119	0.017112
50	189.71	193.67	197.12	2.2015	189.61	193.62	196.89	2.1625	-1.3725	-0.05464	0.8878	0.69102

Device Test: 20.85 FSW_EXT_RT_B(LEVEL|FREQ/RT/14/14/0/1000/5/200kHz//@FSW_EXT_RT_B)

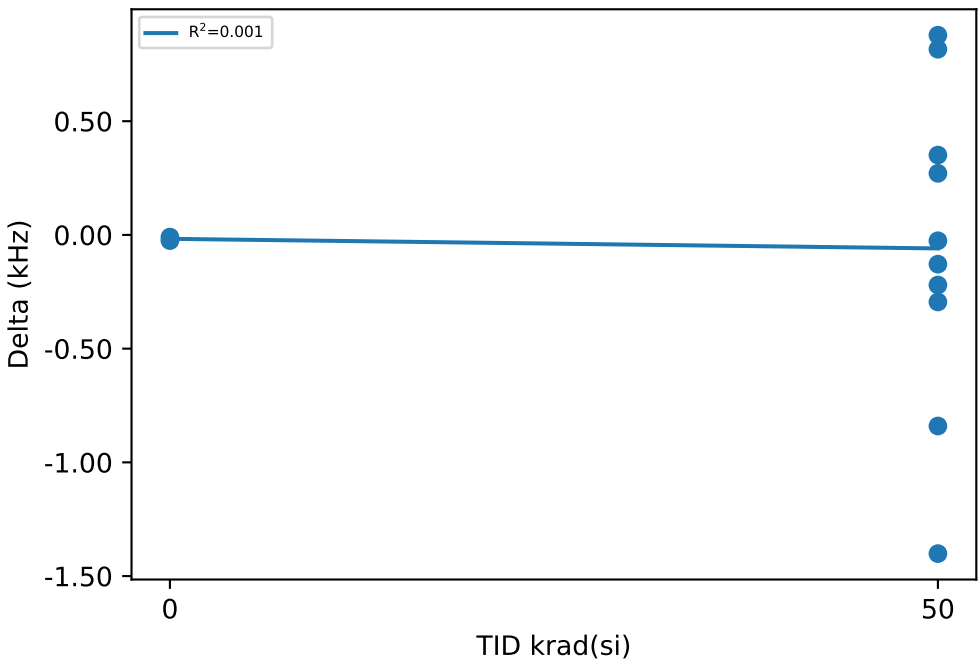
TID vs Result Stats



Test Results (Lower Limit = 180.0, Upper Limit = 220.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	191.95	191.93	-0.0249
2	0	Correlation	193.65	193.64	-0.0094
4	50	Bias	195.18	194.89	-0.2948
6	50	Bias	189.69	189.56	-0.1286
7	50	Bias	194.31	194.29	-0.0256
8	50	Bias	191.04	191.31	0.2708
9	50	Bias	193.61	194.43	0.8164
11	50	Unbias	197.11	196.89	-0.2203
12	50	Unbias	195.31	195.66	0.3511
13	50	Unbias	193.44	192.04	-1.4011
14	50	Unbias	192.15	193.03	0.8781
15	50	Unbias	194.73	193.89	-0.8401

TID vs Post - Pre Exposure Delta

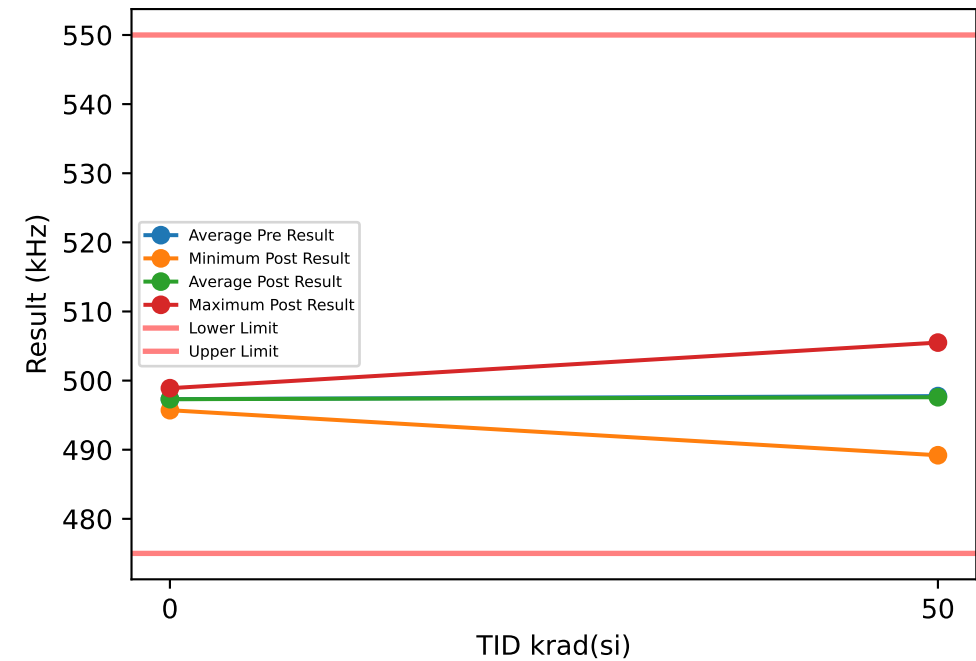


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	191.95	192.8	193.65	1.202	191.93	192.79	193.64	1.213	-0.0249	-0.01715	-0.0094	0.01096
50	189.69	193.66	197.11	2.1983	189.56	193.6	196.89	2.1682	-1.4011	-0.05941	0.8781	0.70082

Device Test: 20.87 FSW_EXT_RT_C(LEVEL|FREQ/RT/4.5/4.5/0/1000/4.5/500kHz//@FSW_EXT_RT_C)

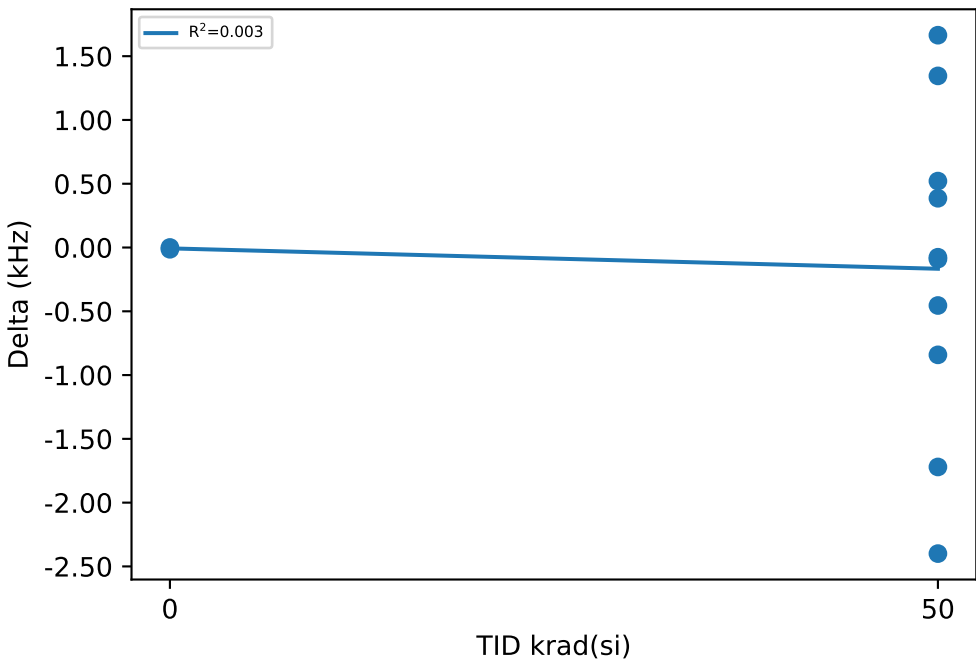
TID vs Result Stats



Test Results (Lower Limit = 475.0, Upper Limit = 550.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	495.73	495.72	-0.0138
2	0	Correlation	498.9	498.9	0.0005
4	50	Bias	499.56	498.71	-0.8414
6	50	Bias	489.65	489.2	-0.4545
7	50	Bias	498.21	498.12	-0.091
8	50	Bias	492.02	492.54	0.5208
9	50	Bias	496.84	498.19	1.3454
11	50	Unbias	505.58	505.5	-0.0761
12	50	Unbias	502.03	502.42	0.3862
13	50	Unbias	499.02	496.62	-2.3995
14	50	Unbias	494.67	496.34	1.6645
15	50	Unbias	500	498.28	-1.7203

TID vs Post - Pre Exposure Delta

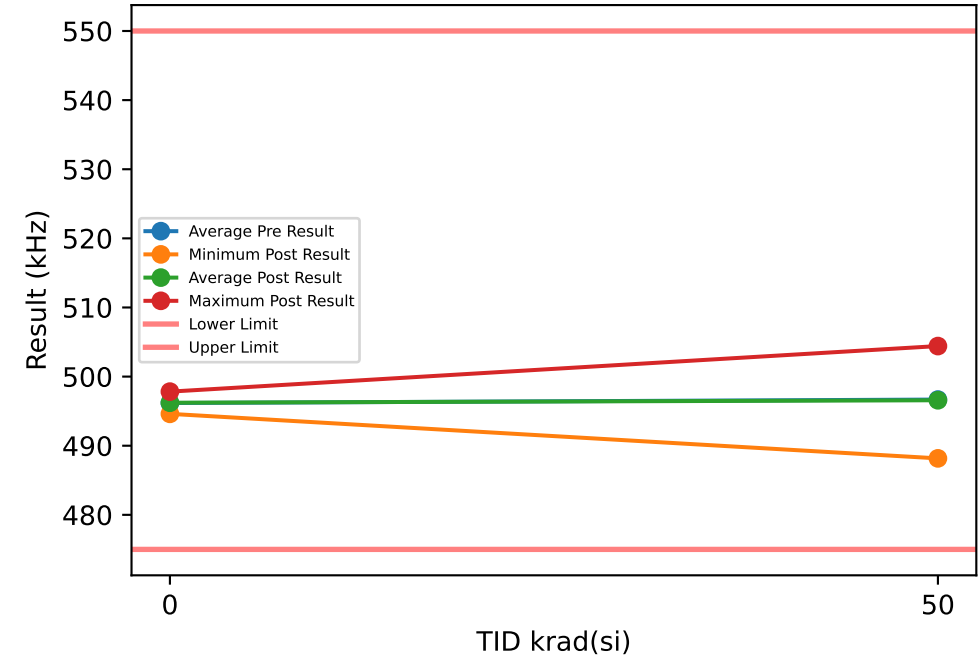


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	495.73	497.32	498.9	2.2425	495.72	497.31	498.9	2.2526	-0.0138	-0.00665	0.0005	0.010112
50	489.65	497.76	505.58	4.6941	489.2	497.59	505.5	4.5535	-2.3995	-0.16659	1.6645	1.2636

Device Test: 20.89 FSW_EXT_RT_C(LEVEL|FREQ/RT/5/5/0/1000/5/500kHz//@FSW_EXT_RT_C)

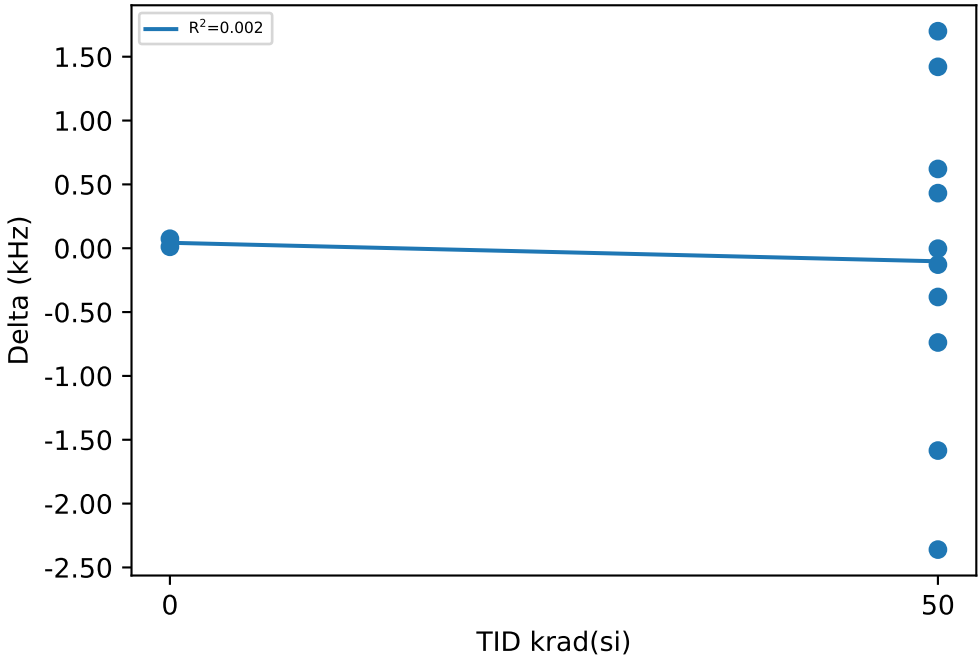
TID vs Result Stats



Test Results (Lower Limit = 475.0, Upper Limit = 550.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	494.54	494.61	0.0744
2	0	Correlation	497.81	497.82	0.0112
4	50	Bias	498.55	497.81	-0.7382
6	50	Bias	488.55	488.17	-0.3817
7	50	Bias	497.13	497.13	-0.0034
8	50	Bias	490.94	491.56	0.6211
9	50	Bias	495.8	497.22	1.4207
11	50	Unbias	504.55	504.42	-0.1285
12	50	Unbias	500.89	501.33	0.4316
13	50	Unbias	497.84	495.48	-2.3602
14	50	Unbias	493.66	495.36	1.6998
15	50	Unbias	498.87	497.29	-1.5846

TID vs Post - Pre Exposure Delta

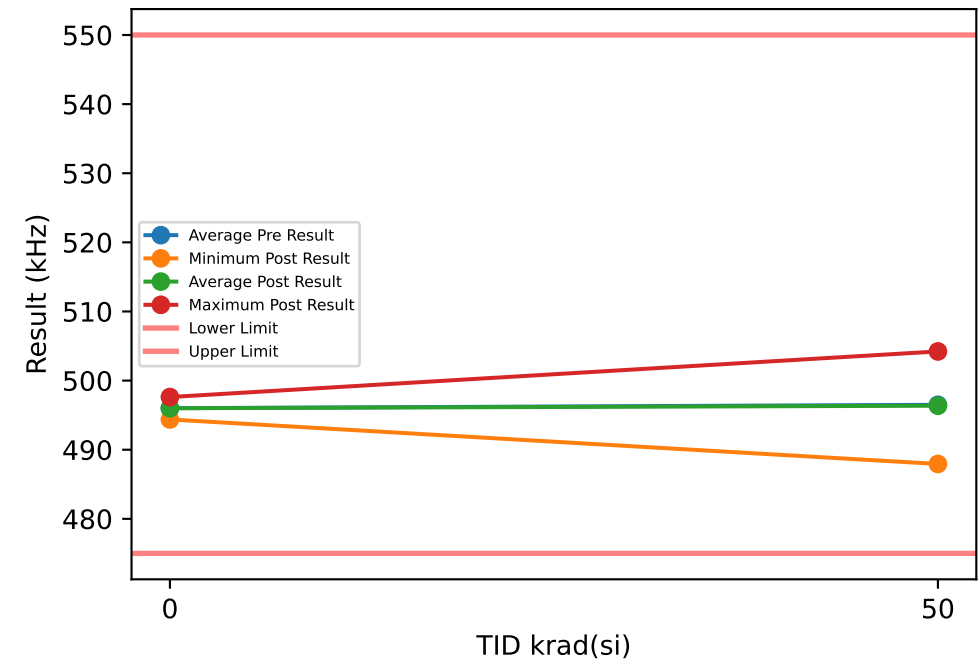


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	494.54	496.18	497.81	2.317	494.61	496.22	497.82	2.2723	0.0112	0.0428	0.0744	0.044689
50	488.55	496.68	504.55	4.6955	488.17	496.58	504.42	4.5377	-2.3602	-0.10234	1.6998	1.2545

Device Test: 20.91 FSW_EXT_RT_C(LEVEL|FREQ/RT/12/12/0/1000/5/500kHz//@FSW_EXT_RT_C)

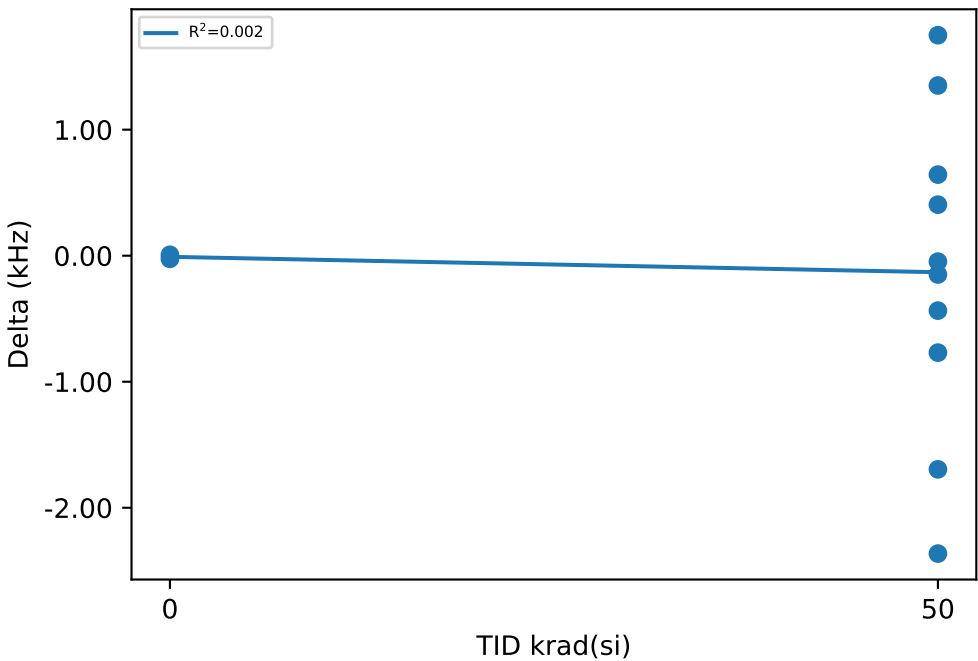
TID vs Result Stats



Test Results (Lower Limit = 475.0, Upper Limit = 550.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	494.4	494.38	-0.0249
2	0	Correlation	497.62	497.62	0.0071
4	50	Bias	498.32	497.55	-0.7692
6	50	Bias	488.37	487.94	-0.4358
7	50	Bias	496.92	496.87	-0.0471
8	50	Bias	490.74	491.38	0.6435
9	50	Bias	495.62	496.98	1.3507
11	50	Unbias	504.37	504.22	-0.1491
12	50	Unbias	500.8	501.2	0.4051
13	50	Unbias	497.65	495.29	-2.3637
14	50	Unbias	493.46	495.21	1.7496
15	50	Unbias	498.71	497.02	-1.6951

TID vs Post - Pre Exposure Delta

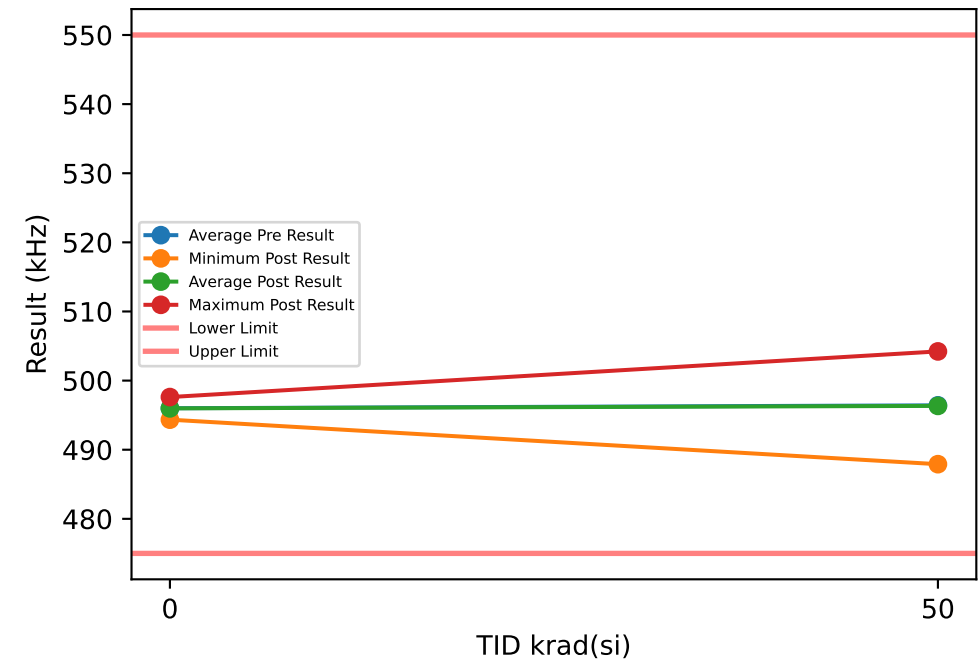


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	494.4	496.01	497.62	2.2717	494.38	496	497.62	2.2943	-0.0249	-0.0089	0.0071	0.022627
50	488.37	496.5	504.37	4.7059	487.94	496.37	504.22	4.5443	-2.3637	-0.13111	1.7496	1.2718

Device Test: 20.93 FSW_EXT_RT_C(LEVEL|FREQ/RT/14/14/0/1000/5/500kHz//@FSW_EXT_RT_C)

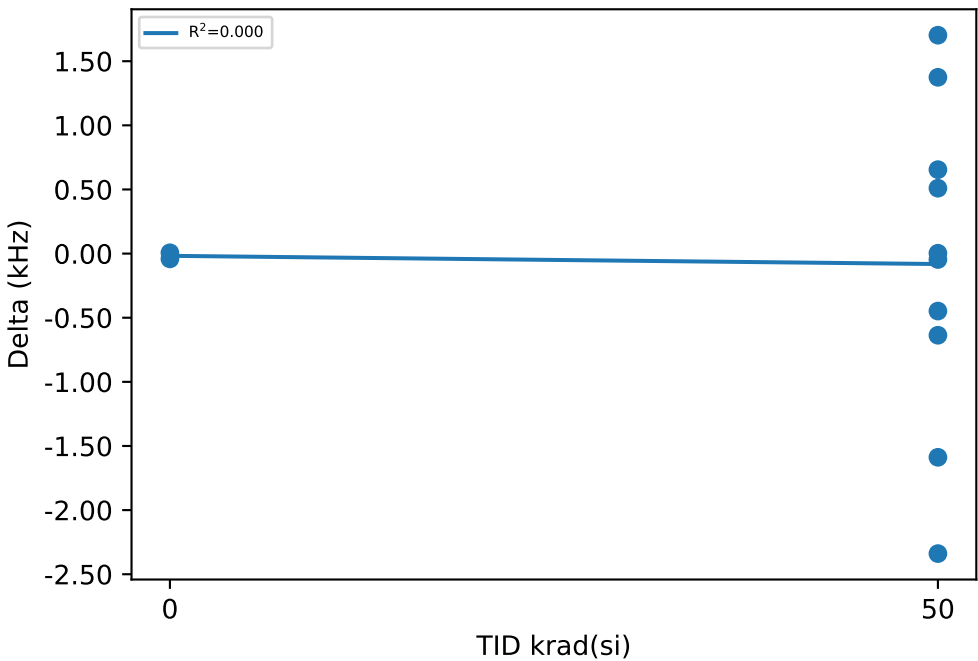
TID vs Result Stats



Test Results (Lower Limit = 475.0, Upper Limit = 550.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	494.39	494.35	-0.0412
2	0	Correlation	497.61	497.62	0.0063
4	50	Bias	498.22	497.58	-0.6367
6	50	Bias	488.36	487.91	-0.4481
7	50	Bias	496.84	496.84	0.0029
8	50	Bias	490.69	491.34	0.6545
9	50	Bias	495.57	496.94	1.3745
11	50	Unbias	504.27	504.22	-0.0461
12	50	Unbias	500.66	501.17	0.5098
13	50	Unbias	497.61	495.27	-2.3391
14	50	Unbias	493.4	495.1	1.7028
15	50	Unbias	498.61	497.02	-1.5883

TID vs Post - Pre Exposure Delta

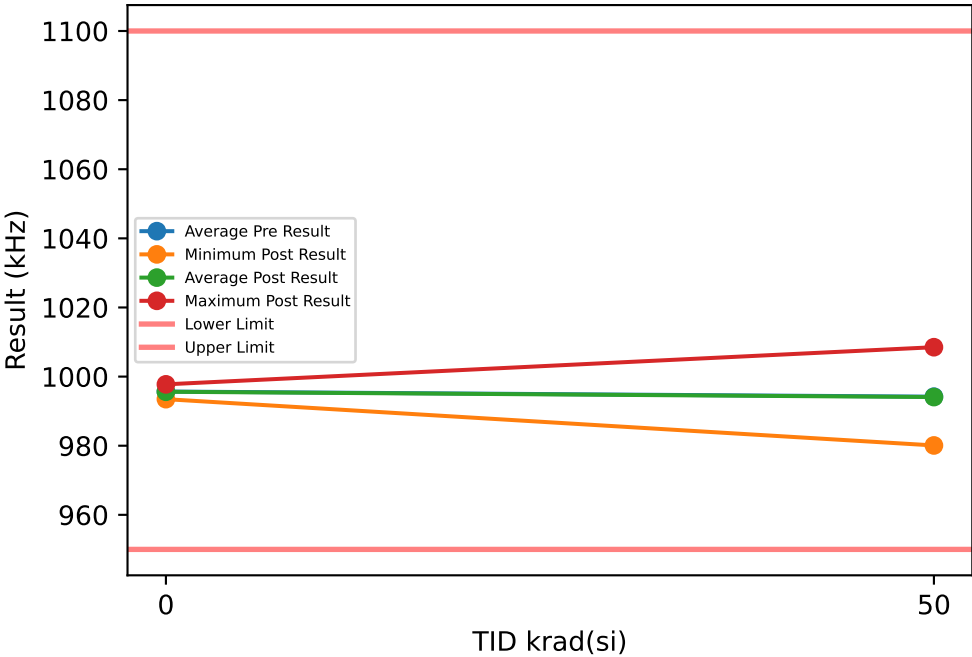


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	494.39	496	497.61	2.2786	494.35	495.98	497.62	2.3122	-0.0412	-0.01745	0.0063	0.033588
50	488.36	496.42	504.27	4.6783	487.91	496.34	504.22	4.5568	-2.3391	-0.08138	1.7028	1.2478

Device Test: 20.95 FSW_EXT_RT_D(LEVEL|FREQ/RT/4.5/4.5/0/1000/4.5/1MHz//@FSW_EXT_RT_D)

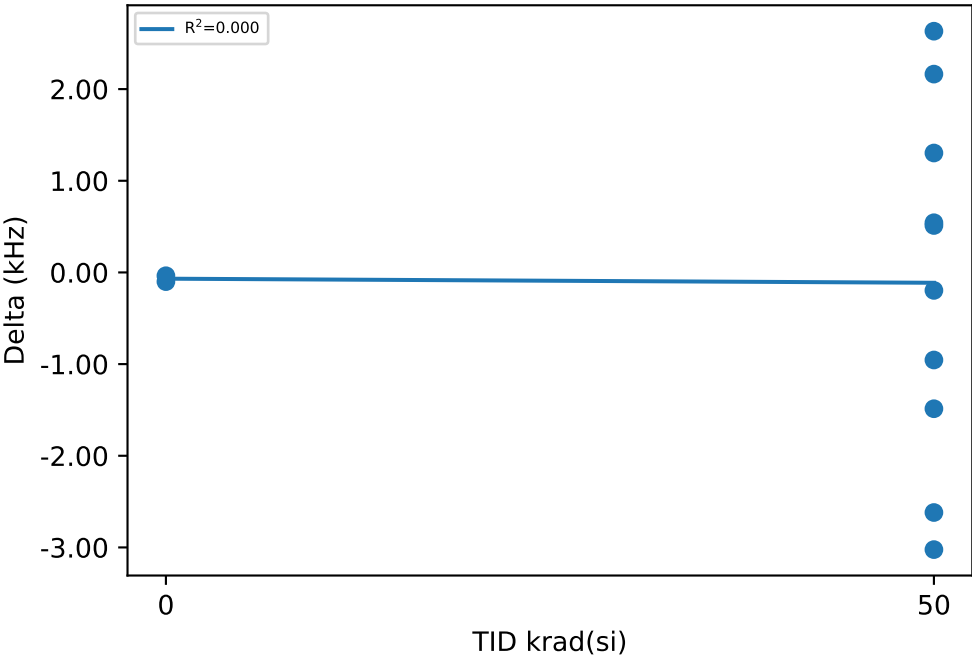
TID vs Result Stats



Test Results (Lower Limit = 950.0, Upper Limit = 1100.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	993.57	993.47	-0.1002
2	0	Correlation	997.79	997.76	-0.0361
4	50	Bias	996.26	994.77	-1.4869
6	50	Bias	981.03	980.08	-0.9552
7	50	Bias	994.5	994.31	-0.196
8	50	Bias	983.61	984.91	1.3029
9	50	Bias	991.45	993.61	2.1636
11	50	Unbias	1008	1008.5	0.5421
12	50	Unbias	1002	1002.5	0.5122
13	50	Unbias	998.11	995.09	-3.0236
14	50	Unbias	988.71	991.34	2.6317
15	50	Unbias	998.3	995.68	-2.619

TID vs Post - Pre Exposure Delta

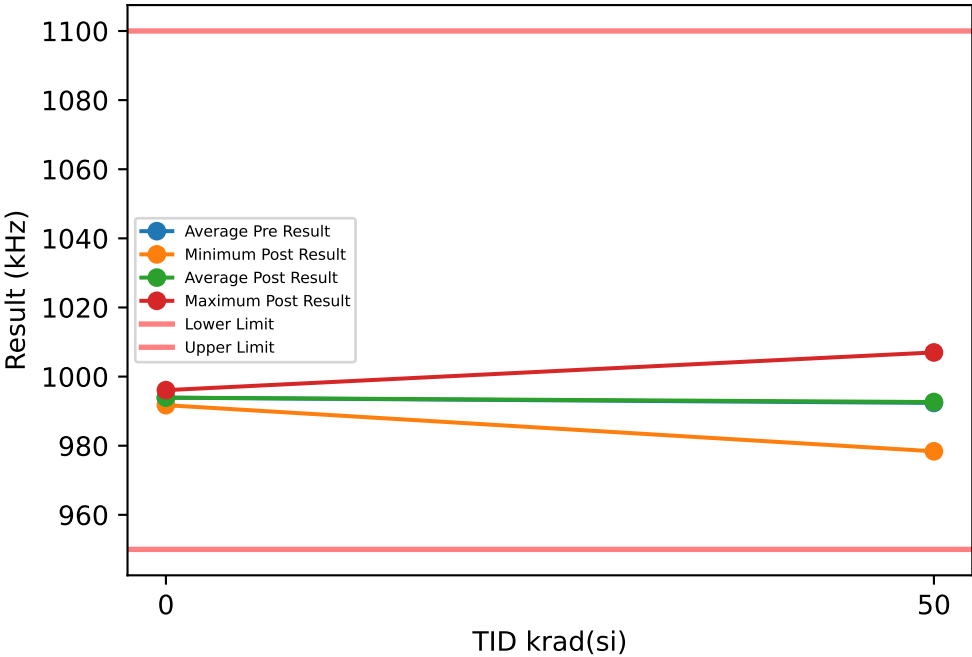


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	993.57	995.68	997.79	2.986	993.47	995.61	997.76	3.0314	-0.1002	-0.06815	-0.0361	0.045326
50	981.03	994.19	1008	8.2303	980.08	994.08	1008.5	7.9636	-3.0236	-0.11282	2.6317	1.9118

Device Test: 20.97 FSW_EXT_RT_D(LEVEL|FREQ/RT/5/5/0/1000/5/1MHz//@FSW_EXT_RT_D)

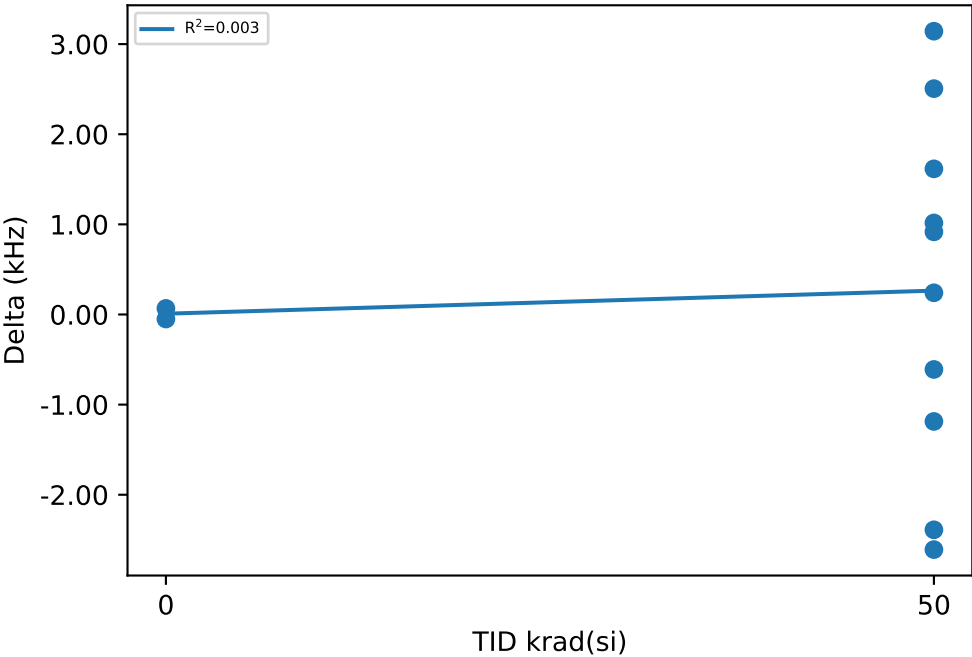
TID vs Result Stats



Test Results (Lower Limit = 950.0, Upper Limit = 1100.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	991.79	991.74	-0.0502
2	0	Correlation	996.01	996.08	0.0675
4	50	Bias	994.62	993.44	-1.1867
6	50	Bias	978.99	978.38	-0.6098
7	50	Bias	992.5	992.74	0.2407
8	50	Bias	982.01	983.63	1.616
9	50	Bias	989.69	992.2	2.506
11	50	Unbias	1006.1	1007	0.9166
12	50	Unbias	1000.2	1001.3	1.0157
13	50	Unbias	996.18	993.57	-2.6086
14	50	Unbias	986.86	990.01	3.1432
15	50	Unbias	996.64	994.25	-2.3889

TID vs Post - Pre Exposure Delta

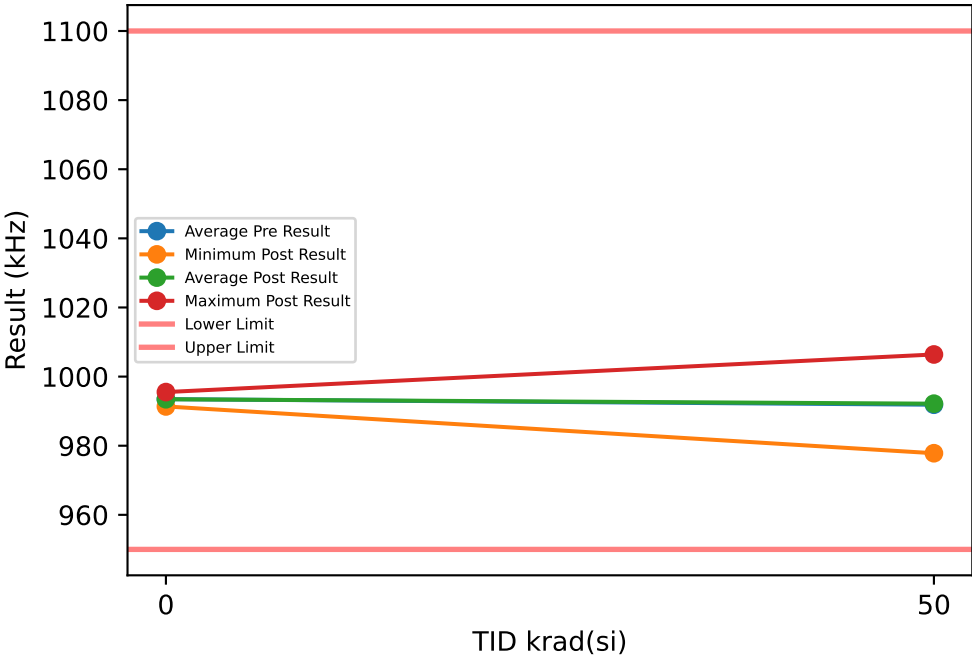


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	991.79	993.9	996.01	2.985	991.74	993.91	996.08	3.0682	-0.0502	0.00865	0.0675	0.083226
50	978.99	992.38	1006.1	8.2423	978.38	992.65	1007	8	-2.6086	0.26442	3.1432	1.952

Device Test: 20.99 FSW_EXT_RT_D(LEVEL|FREQ/RT/12/12/0/1000/5/1MHz//@FSW_EXT_RT_D)

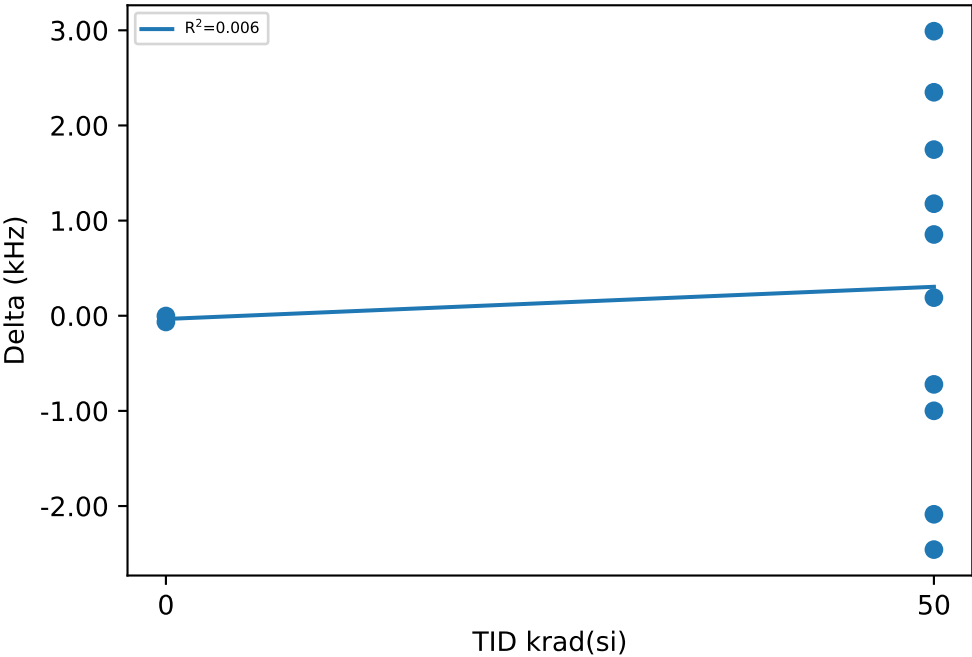
TID vs Result Stats



Test Results (Lower Limit = 950.0, Upper Limit = 1100.0 (kHz))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	991.43	991.36	-0.0654
2	0	Correlation	995.52	995.52	-0.0027
4	50	Bias	994.11	993.11	-0.9991
6	50	Bias	978.55	977.83	-0.7213
7	50	Bias	991.92	992.11	0.1904
8	50	Bias	981.49	983.24	1.7461
9	50	Bias	989.17	991.51	2.3487
11	50	Unbias	1005.5	1006.4	0.8541
12	50	Unbias	999.61	1000.8	1.1776
13	50	Unbias	995.65	993.19	-2.4577
14	50	Unbias	986.46	989.45	2.9906
15	50	Unbias	996.1	994.01	-2.0866

TID vs Post - Pre Exposure Delta

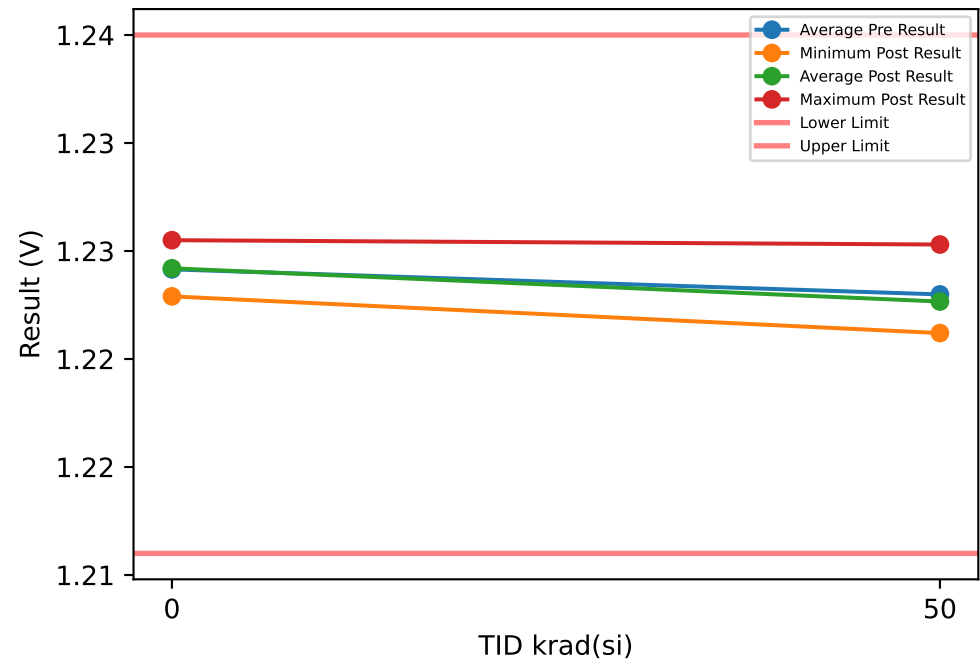


Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	991.43	993.48	995.52	2.8948	991.36	993.44	995.52	2.9392	-0.0654	-0.03405	-0.0027	0.044336
50	978.55	991.86	1005.5	8.2047	977.83	992.17	1006.4	7.9958	-2.4577	0.30428	2.9906	1.8454

Device Test: 21.1 V_REFCAP(VOLTAGE|VREF/VREF/4.5/4.5/0/0/4.5/100kHz//@V_REFCAP)

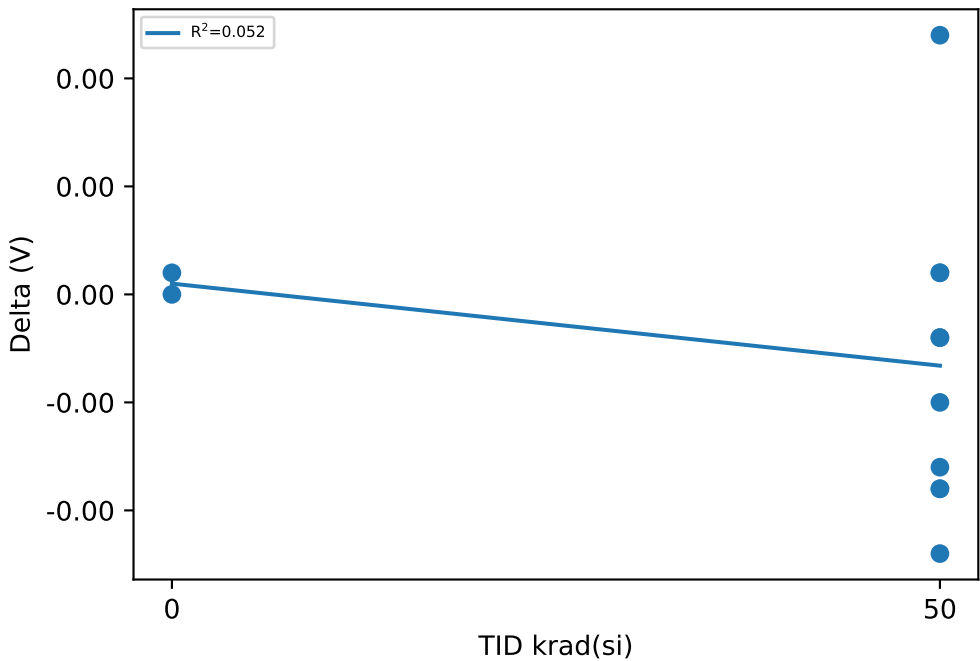
TID vs Result Stats



Test Results (Lower Limit = 1.211, Upper Limit = 1.235 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.2228	1.2229	0.0001
2	0	Correlation	1.2255	1.2255	0
4	50	Bias	1.2235	1.2223	-0.0012
6	50	Bias	1.2226	1.2217	-0.0009
7	50	Bias	1.2252	1.2253	0.0001
8	50	Bias	1.2239	1.2231	-0.0008
9	50	Bias	1.2257	1.2252	-0.0005
11	50	Unbias	1.2224	1.2225	0.0001
12	50	Unbias	1.2215	1.2213	-0.0002
13	50	Unbias	1.2214	1.2212	-0.0002
14	50	Unbias	1.2221	1.2212	-0.0009
15	50	Unbias	1.2216	1.2228	0.0012

TID vs Post - Pre Exposure Delta

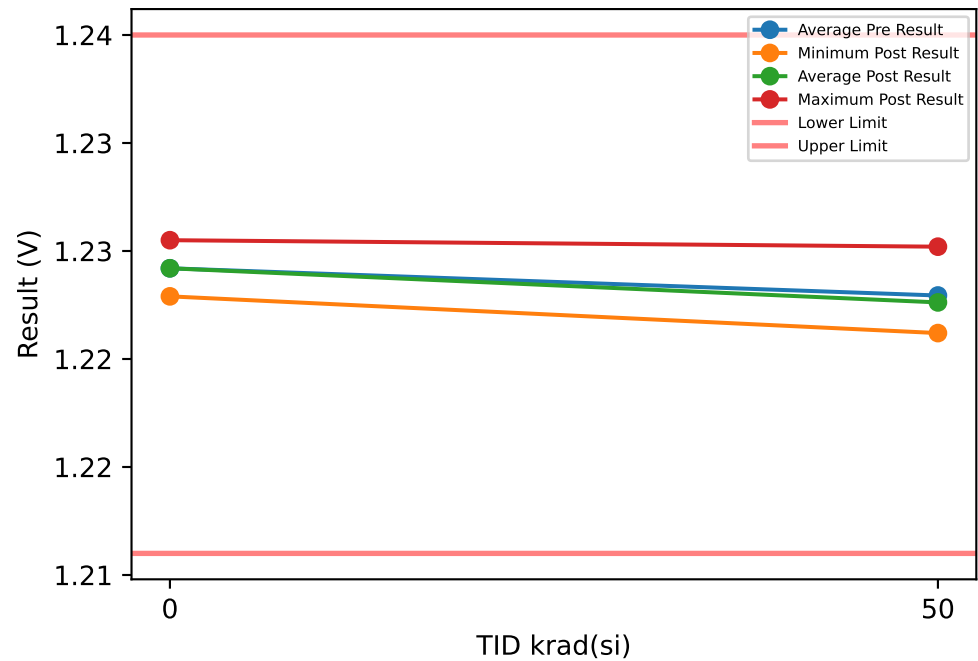


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2228	1.2242	1.2255	0.0019092	1.2229	1.2242	1.2255	0.0018385	0	5e-05	0.0001	7.0711e-05
50	1.2214	1.223	1.2257	0.001538	1.2212	1.2227	1.2253	0.0015211	-0.0012	-0.00033	0.0012	0.00069929

Device Test: 21.11 V_REFCAP(VOLTAGE|VREF/VREF/5/5/0/0/5/500kHz//@V_REFCAP)

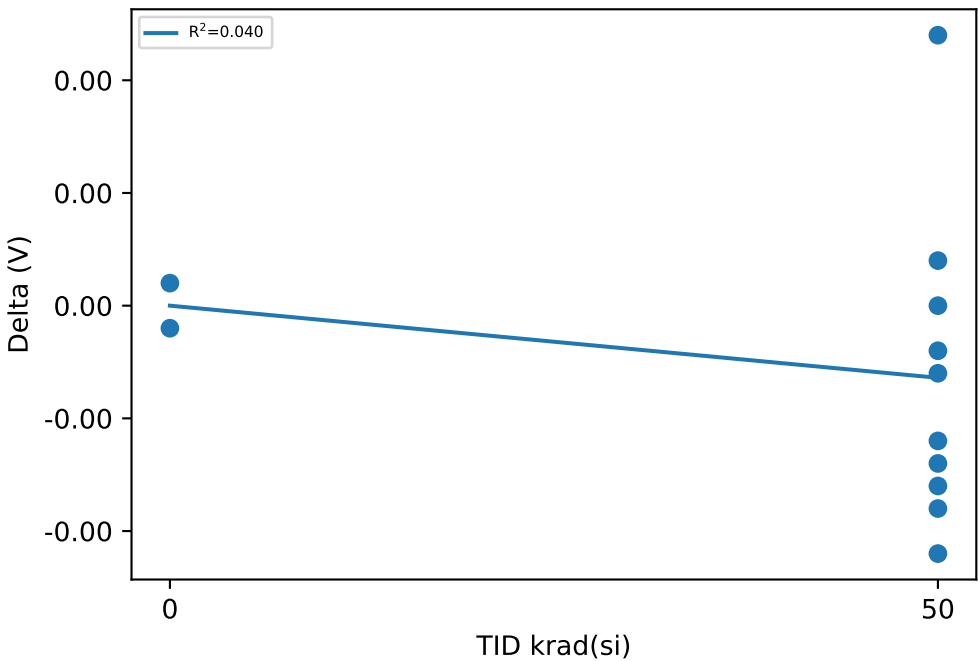
TID vs Result Stats



Test Results (Lower Limit = 1.211, Upper Limit = 1.235 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.2228	1.2229	0.0001
2	0	Correlation	1.2256	1.2255	-0.0001
4	50	Bias	1.2234	1.2223	-0.0011
6	50	Bias	1.2226	1.2217	-0.0009
7	50	Bias	1.2252	1.2252	0
8	50	Bias	1.2238	1.2231	-0.0007
9	50	Bias	1.2257	1.2251	-0.0006
11	50	Unbias	1.2223	1.2225	0.0002
12	50	Unbias	1.2215	1.2212	-0.0003
13	50	Unbias	1.2214	1.2212	-0.0002
14	50	Unbias	1.222	1.2212	-0.0008
15	50	Unbias	1.2215	1.2227	0.0012

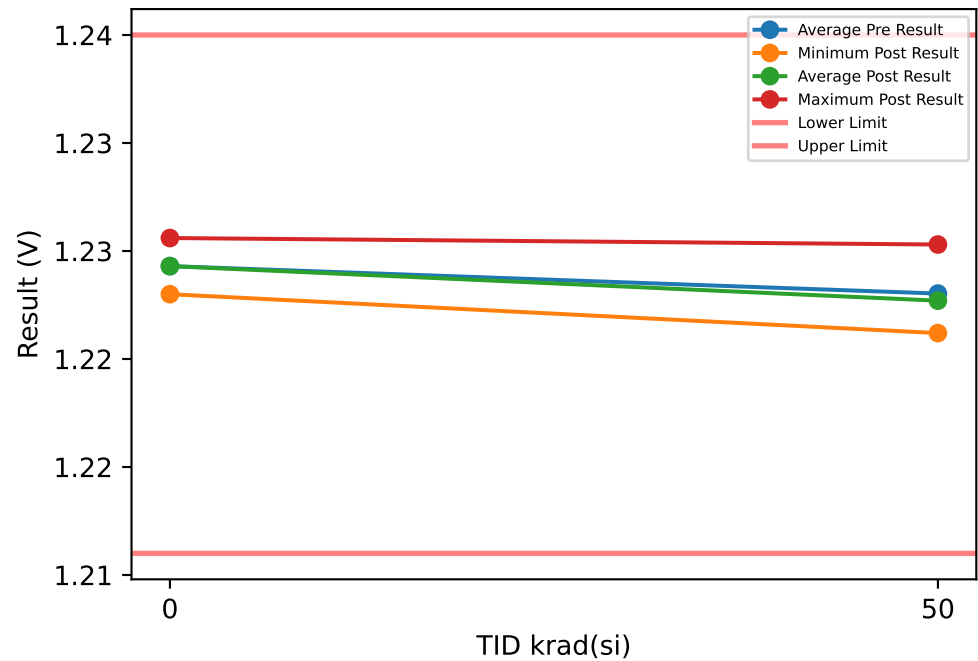
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2228	1.2242	1.2256	0.0019799	1.2229	1.2242	1.2255	0.0018385	-0.0001	0	0.0001	0.00014142
50	1.2214	1.2229	1.2257	0.0015493	1.2212	1.2226	1.2252	0.0014928	-0.0011	-0.00032	0.0012	0.00067462

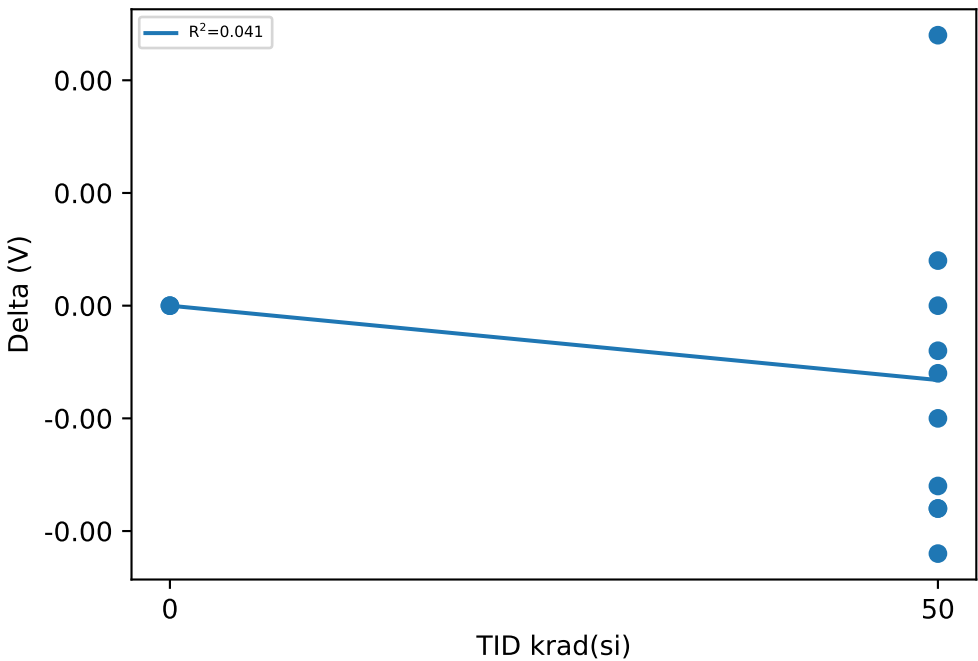
TID vs Result Stats



Test Results (Lower Limit = 1.211, Upper Limit = 1.235 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.223	1.223	0
2	0	Correlation	1.2256	1.2256	0
4	50	Bias	1.2235	1.2224	-0.0011
6	50	Bias	1.2227	1.2218	-0.0009
7	50	Bias	1.2253	1.2253	0
8	50	Bias	1.2239	1.2231	-0.0008
9	50	Bias	1.2257	1.2252	-0.0005
11	50	Unbias	1.2224	1.2226	0.0002
12	50	Unbias	1.2215	1.2213	-0.0002
13	50	Unbias	1.2215	1.2212	-0.0003
14	50	Unbias	1.2222	1.2213	-0.0009
15	50	Unbias	1.2216	1.2228	0.0012

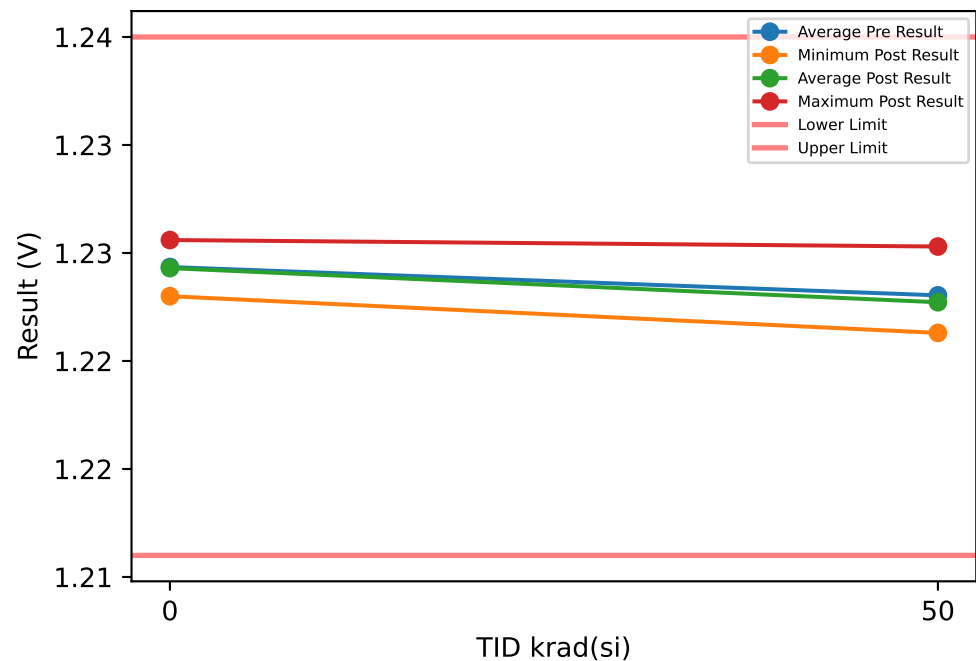
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.223	1.2243	1.2256	0.0018385	1.223	1.2243	1.2256	0.0018385	0	0	0	0
50	1.2215	1.223	1.2257	0.0015341	1.2212	1.2227	1.2253	0.0015004	-0.0011	-0.00033	0.0012	0.00068646

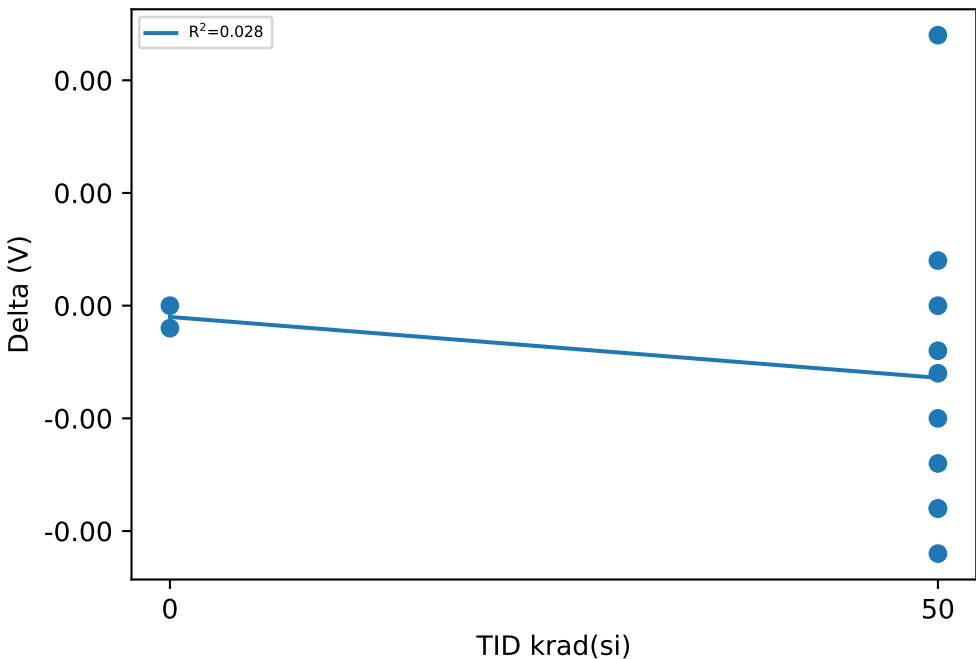
TID vs Result Stats



Test Results (Lower Limit = 1.211, Upper Limit = 1.235 (V))

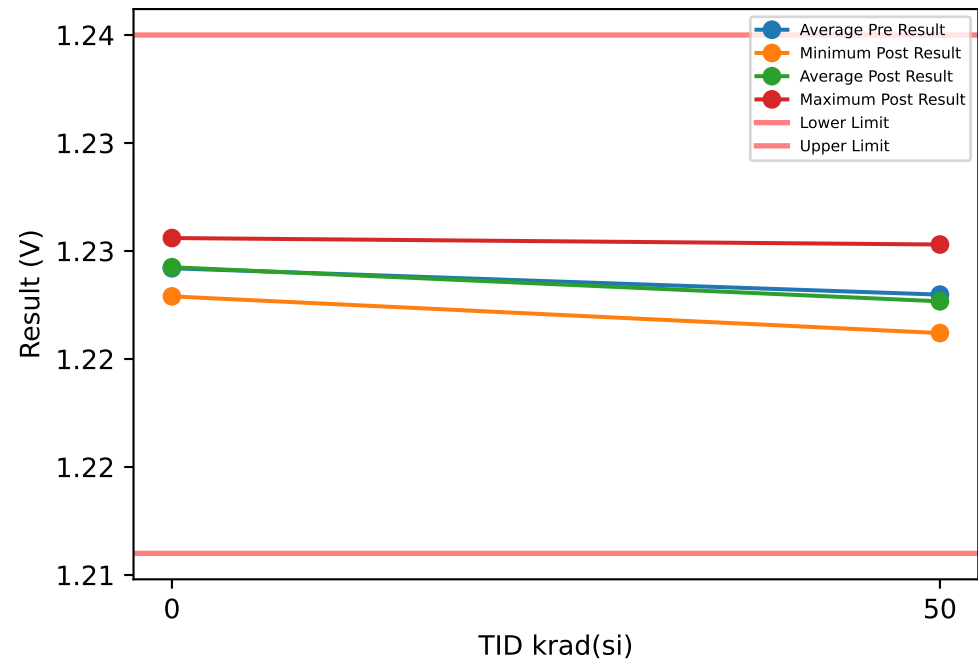
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.223	1.223	0
2	0	Correlation	1.2257	1.2256	-0.0001
4	50	Bias	1.2235	1.2224	-0.0011
6	50	Bias	1.2227	1.2218	-0.0009
7	50	Bias	1.2253	1.2253	0
8	50	Bias	1.2239	1.2232	-0.0007
9	50	Bias	1.2257	1.2252	-0.0005
11	50	Unbias	1.2224	1.2226	0.0002
12	50	Unbias	1.2216	1.2213	-0.0003
13	50	Unbias	1.2215	1.2213	-0.0002
14	50	Unbias	1.2222	1.2213	-0.0009
15	50	Unbias	1.2216	1.2228	0.0012

TID vs Post - Pre Exposure Delta



Device Test: 21.17 V_REFCAP(VOLTAGE|VREF/VREF/4.5/4.5/0/0/4.5/1MHz//@V_REFCAP)

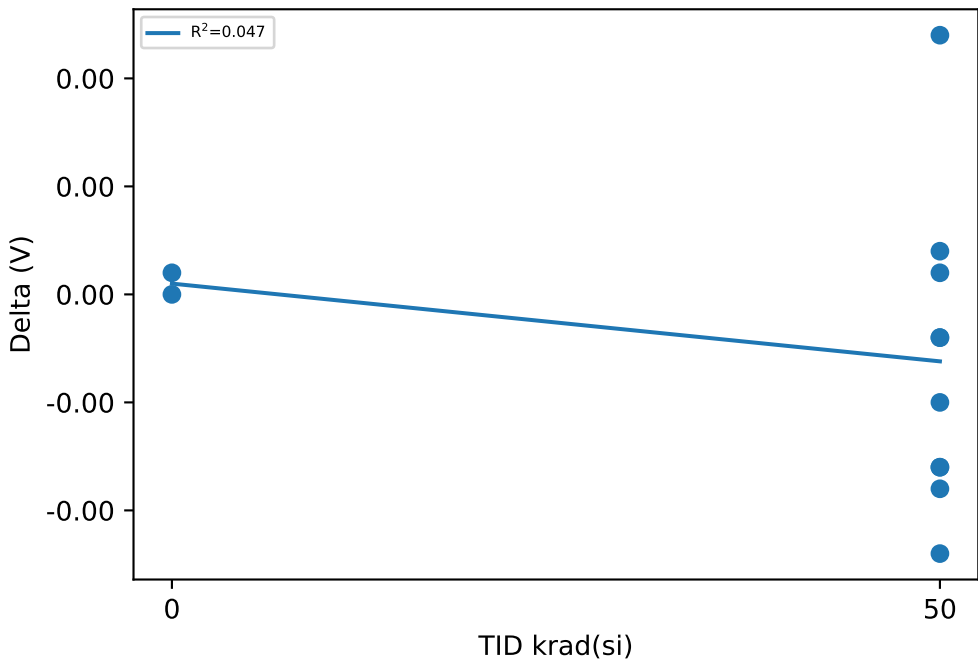
TID vs Result Stats



Test Results (Lower Limit = 1.211, Upper Limit = 1.235 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.2229	1.2229	0
2	0	Correlation	1.2255	1.2256	0.0001
4	50	Bias	1.2235	1.2223	-0.0012
6	50	Bias	1.2226	1.2217	-0.0009
7	50	Bias	1.2252	1.2253	0.0001
8	50	Bias	1.2239	1.2231	-0.0008
9	50	Bias	1.2257	1.2252	-0.0005
11	50	Unbias	1.2223	1.2225	0.0002
12	50	Unbias	1.2215	1.2213	-0.0002
13	50	Unbias	1.2214	1.2212	-0.0002
14	50	Unbias	1.2221	1.2213	-0.0008
15	50	Unbias	1.2216	1.2228	0.0012

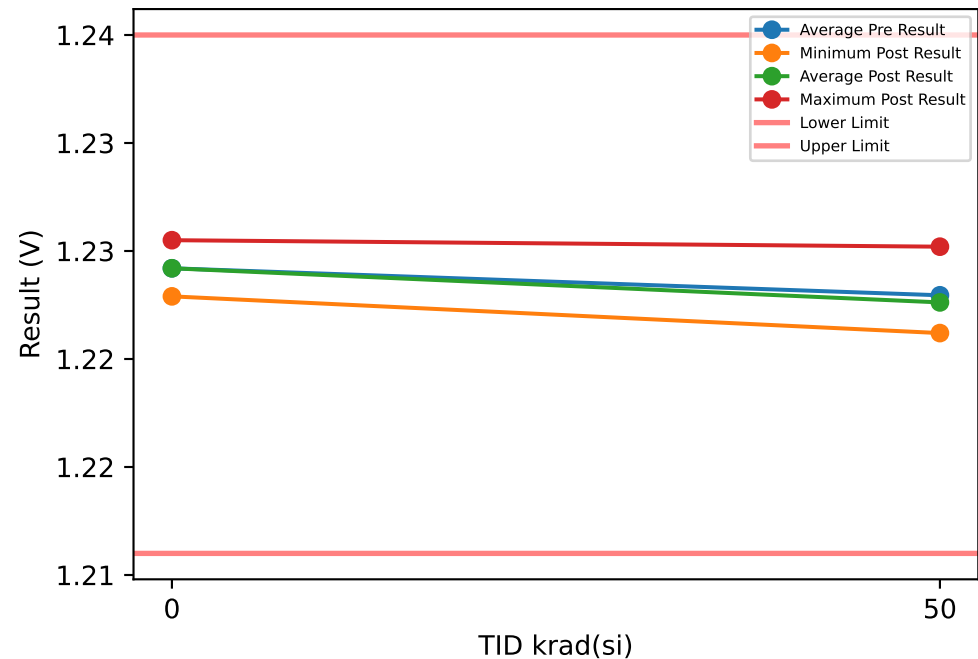
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2229	1.2242	1.2255	0.0018385	1.2229	1.2243	1.2256	0.0019092	0	5e-05	0.0001	7.0711e-05
50	1.2214	1.223	1.2257	0.0015426	1.2212	1.2227	1.2253	0.0015107	-0.0012	-0.00031	0.0012	0.00069833

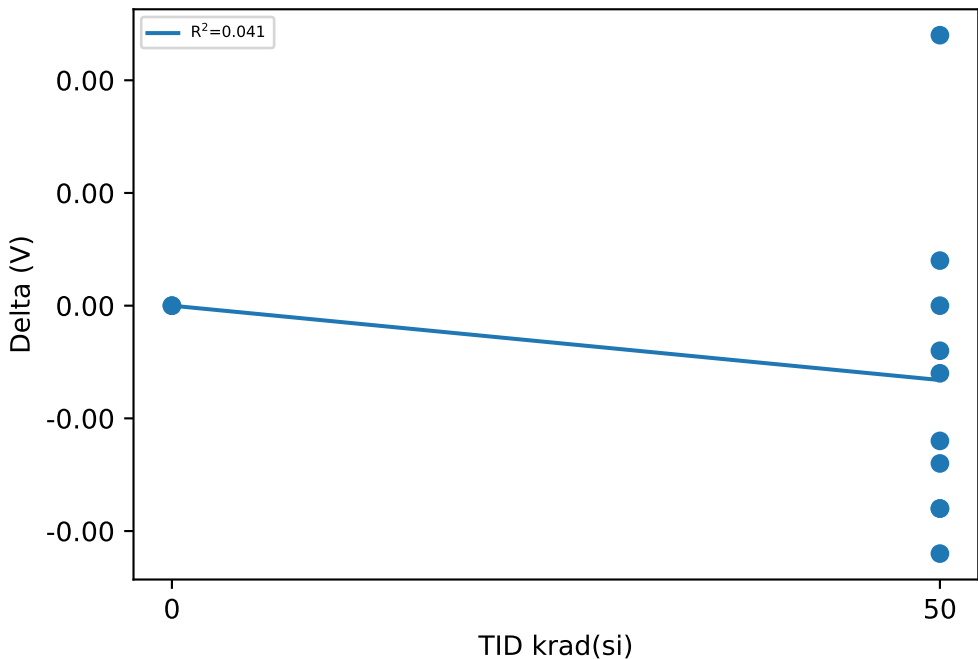
TID vs Result Stats



Test Results (Lower Limit = 1.211, Upper Limit = 1.235 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.2229	1.2229	0
2	0	Correlation	1.2255	1.2255	0
4	50	Bias	1.2234	1.2223	-0.0011
6	50	Bias	1.2226	1.2217	-0.0009
7	50	Bias	1.2252	1.2252	0
8	50	Bias	1.2238	1.2231	-0.0007
9	50	Bias	1.2257	1.2251	-0.0006
11	50	Unbias	1.2223	1.2225	0.0002
12	50	Unbias	1.2215	1.2212	-0.0003
13	50	Unbias	1.2214	1.2212	-0.0002
14	50	Unbias	1.2221	1.2212	-0.0009
15	50	Unbias	1.2215	1.2227	0.0012

TID vs Post - Pre Exposure Delta

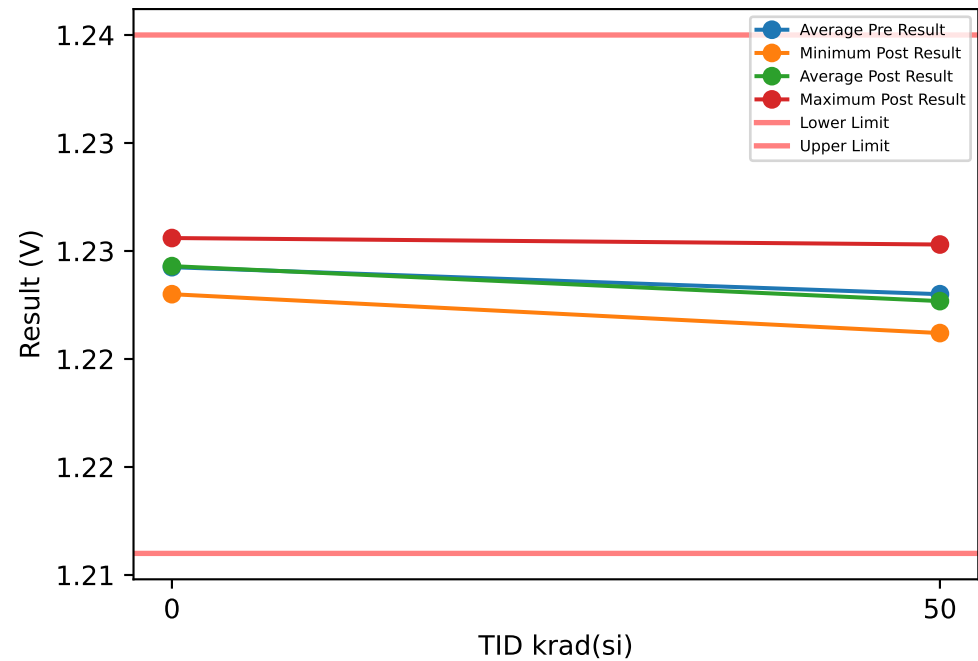


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2229	1.2242	1.2255	0.0018385	1.2229	1.2242	1.2255	0.0018385	0	0	0	0
50	1.2214	1.2229	1.2257	0.0015429	1.2212	1.2226	1.2252	0.0014928	-0.0011	-0.00033	0.0012	0.00068321

Device Test: 21.21 V_REFCAP(VOLTAGE|VREF/VREF/12/12/0/0/5/1MHz//@V_REFCAP)

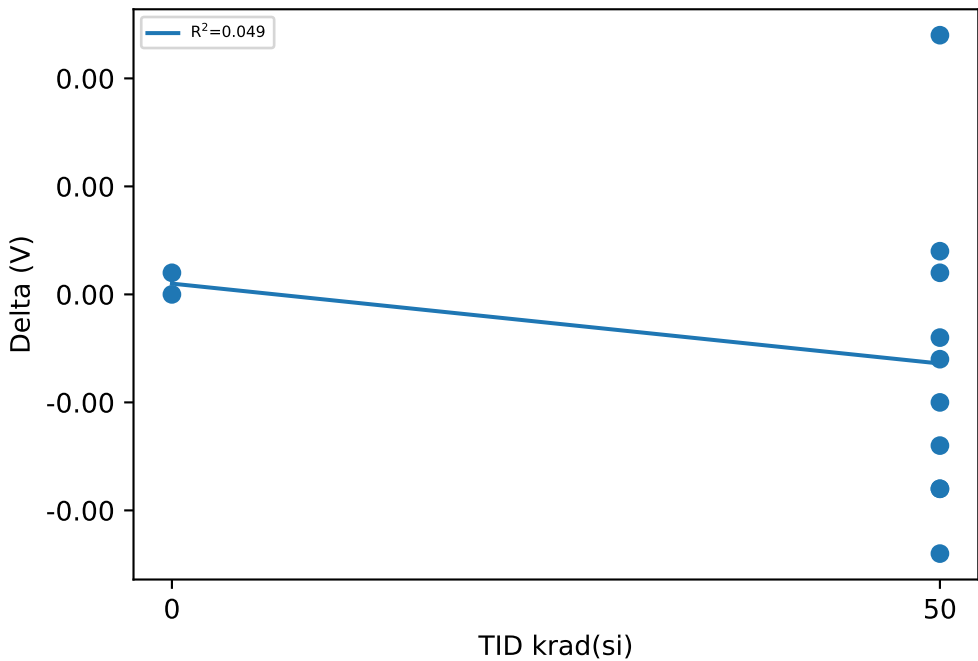
TID vs Result Stats



Test Results (Lower Limit = 1.211, Upper Limit = 1.235 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.2229	1.223	0.0001
2	0	Correlation	1.2256	1.2256	0
4	50	Bias	1.2235	1.2223	-0.0012
6	50	Bias	1.2226	1.2217	-0.0009
7	50	Bias	1.2252	1.2253	0.0001
8	50	Bias	1.2239	1.2232	-0.0007
9	50	Bias	1.2257	1.2252	-0.0005
11	50	Unbias	1.2224	1.2226	0.0002
12	50	Unbias	1.2215	1.2212	-0.0003
13	50	Unbias	1.2214	1.2212	-0.0002
14	50	Unbias	1.2222	1.2213	-0.0009
15	50	Unbias	1.2216	1.2228	0.0012

TID vs Post - Pre Exposure Delta

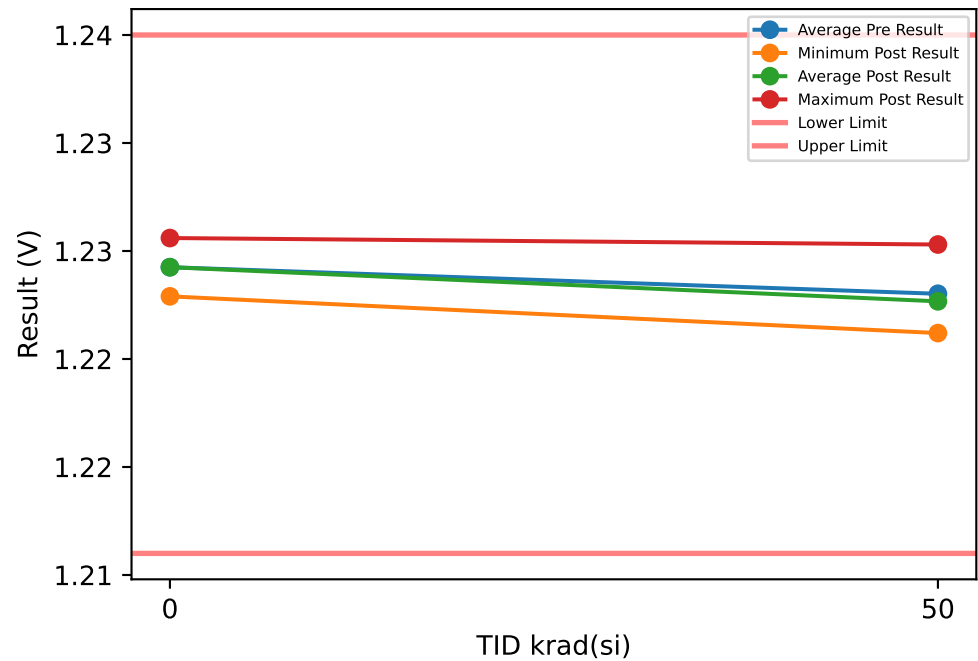


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2229	1.2243	1.2256	0.0019092	1.223	1.2243	1.2256	0.0018385	0	5e-05	0.0001	7.0711e-05
50	1.2214	1.223	1.2257	0.0015319	1.2212	1.2227	1.2253	0.0015237	-0.0012	-0.00032	0.0012	0.00069889

Device Test: 21.23 V_REFCAP(VOLTAGE|VREF/VREF/14/14/0/0/5/1MHz//@V_REFCAP)

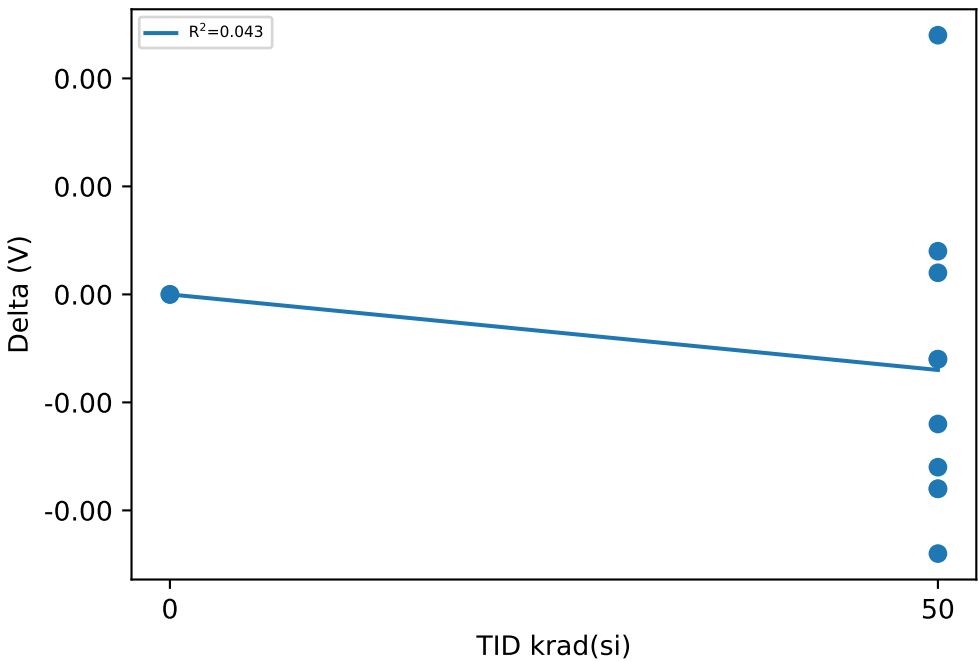
TID vs Result Stats



Test Results (Lower Limit = 1.211, Upper Limit = 1.235 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.2229	1.2229	0
2	0	Correlation	1.2256	1.2256	0
4	50	Bias	1.2235	1.2223	-0.0012
6	50	Bias	1.2226	1.2217	-0.0009
7	50	Bias	1.2252	1.2253	0.0001
8	50	Bias	1.2239	1.2231	-0.0008
9	50	Bias	1.2258	1.2252	-0.0006
11	50	Unbias	1.2224	1.2226	0.0002
12	50	Unbias	1.2215	1.2212	-0.0003
13	50	Unbias	1.2215	1.2212	-0.0003
14	50	Unbias	1.2222	1.2213	-0.0009
15	50	Unbias	1.2216	1.2228	0.0012

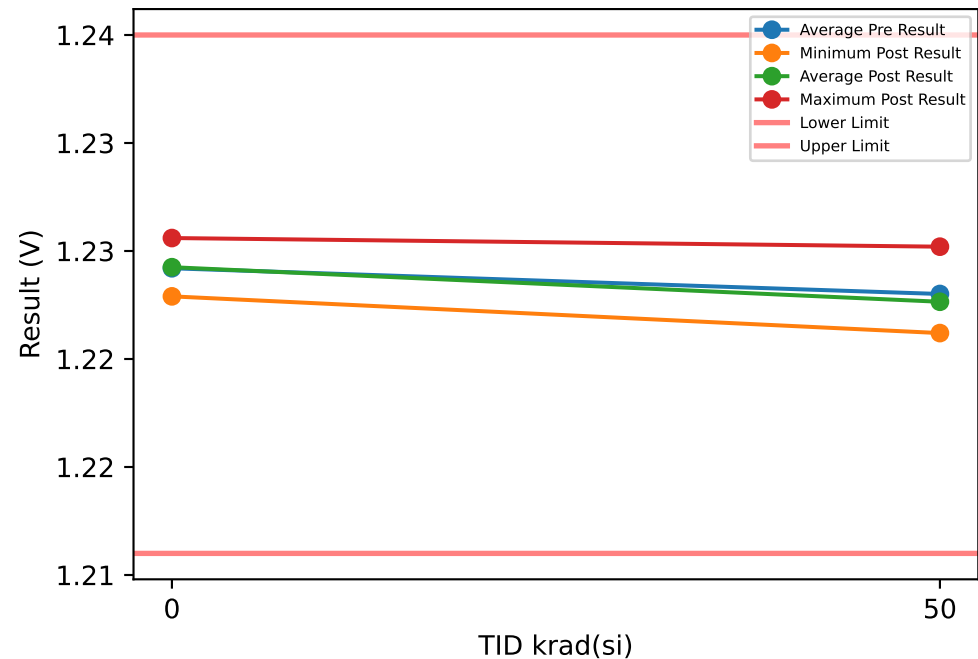
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2229	1.2243	1.2256	0.0019092	1.2229	1.2243	1.2256	0.0019092	0	0	0	0
50	1.2215	1.223	1.2258	0.0015404	1.2212	1.2227	1.2253	0.0015203	-0.0012	-0.00035	0.0012	0.0007075

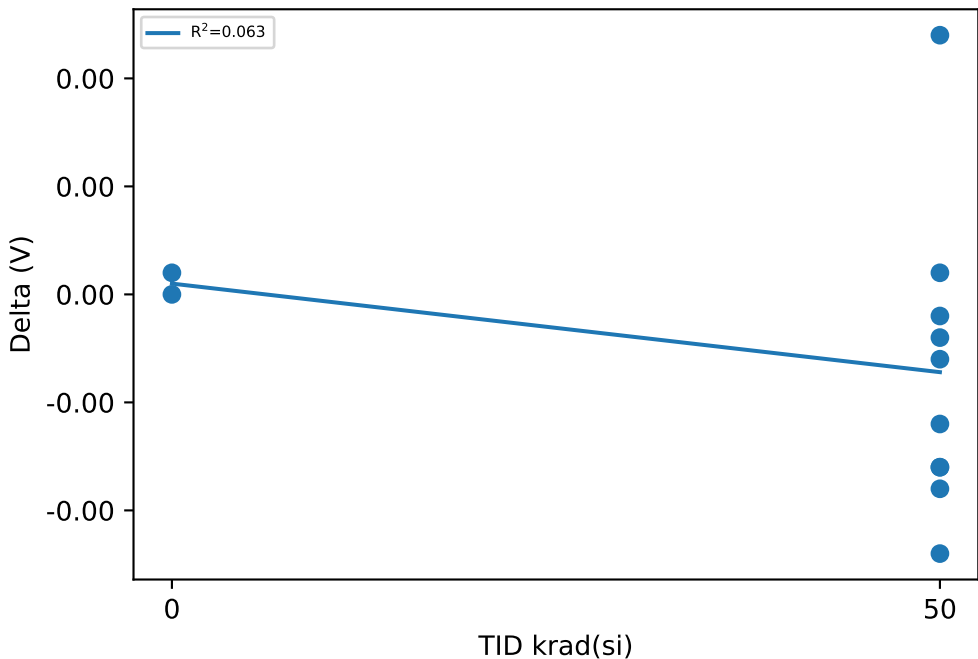
TID vs Result Stats



Test Results (Lower Limit = 1.211, Upper Limit = 1.235 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.2229	1.2229	0
2	0	Correlation	1.2255	1.2256	0.0001
4	50	Bias	1.2235	1.2223	-0.0012
6	50	Bias	1.2226	1.2217	-0.0009
7	50	Bias	1.2253	1.2252	-0.0001
8	50	Bias	1.2239	1.2231	-0.0008
9	50	Bias	1.2257	1.2251	-0.0006
11	50	Unbias	1.2224	1.2225	0.0001
12	50	Unbias	1.2215	1.2213	-0.0002
13	50	Unbias	1.2215	1.2212	-0.0003
14	50	Unbias	1.2221	1.2213	-0.0008
15	50	Unbias	1.2216	1.2228	0.0012

TID vs Post - Pre Exposure Delta

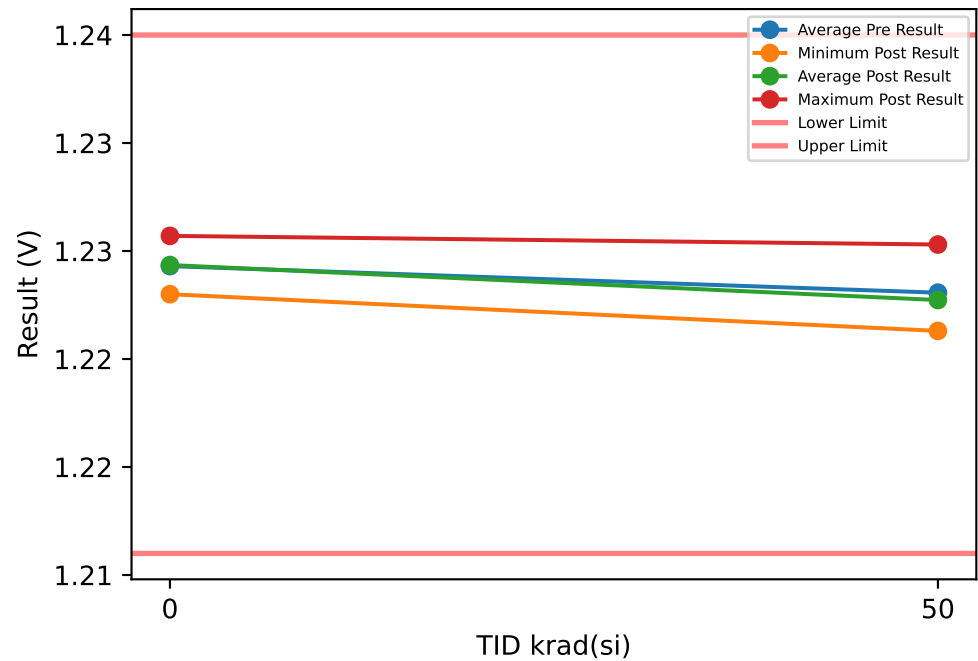


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2229	1.2242	1.2255	0.0018385	1.2229	1.2243	1.2256	0.0019092	0	5e-05	0.0001	7.0711e-05
50	1.2215	1.223	1.2257	0.001543	1.2212	1.2227	1.2252	0.0014729	-0.0012	-0.00036	0.0012	0.00068183

Device Test: 21.29 V_REFCAP(VOLTAGE|VREF/VREF/12/12/0/1000/5/100kHz//@V_REFCAP)

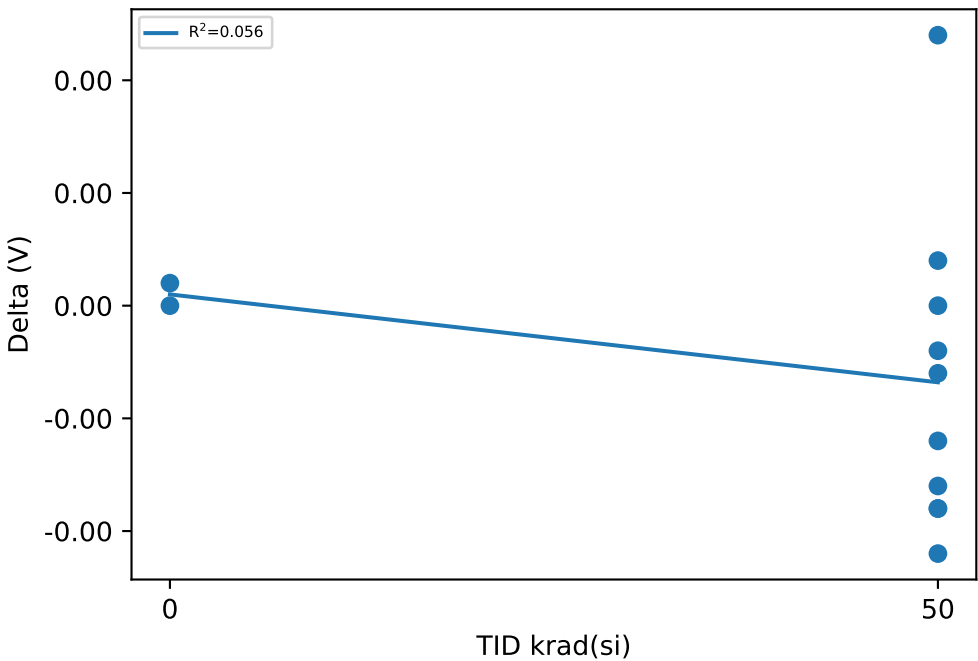
TID vs Result Stats



Test Results (Lower Limit = 1.211, Upper Limit = 1.235 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.223	1.223	0
2	0	Correlation	1.2256	1.2257	0.0001
4	50	Bias	1.2235	1.2224	-0.0011
6	50	Bias	1.2227	1.2218	-0.0009
7	50	Bias	1.2253	1.2253	0
8	50	Bias	1.224	1.2232	-0.0008
9	50	Bias	1.2258	1.2252	-0.0006
11	50	Unbias	1.2224	1.2226	0.0002
12	50	Unbias	1.2216	1.2213	-0.0003
13	50	Unbias	1.2215	1.2213	-0.0002
14	50	Unbias	1.2222	1.2213	-0.0009
15	50	Unbias	1.2217	1.2229	0.0012

TID vs Post - Pre Exposure Delta

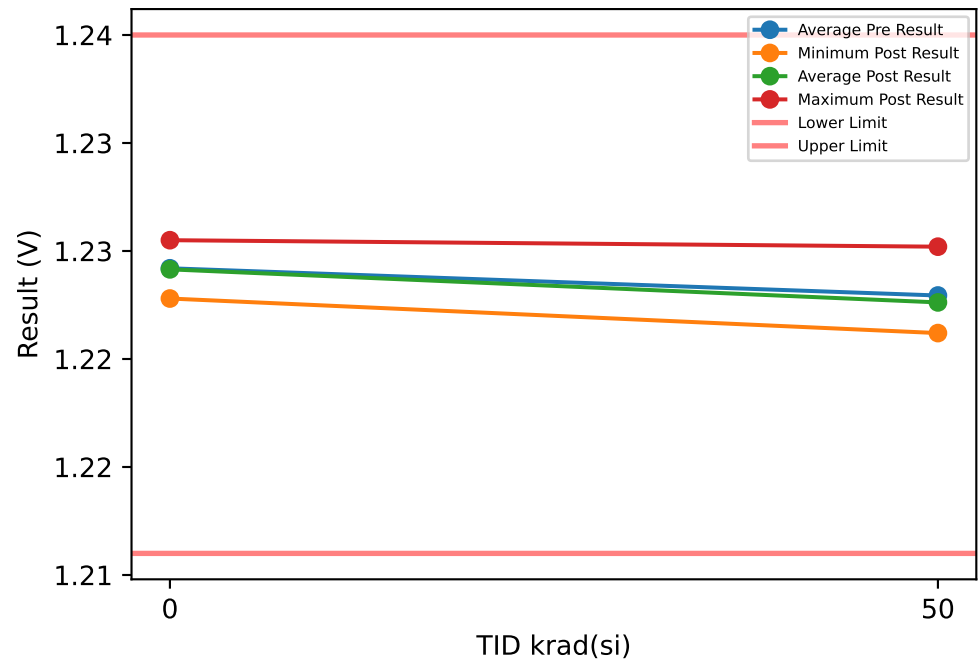


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.223	1.2243	1.2256	0.0018385	1.223	1.2244	1.2257	0.0019092	0	5e-05	0.0001	7.0711e-05
50	1.2215	1.2231	1.2258	0.0015392	1.2213	1.2227	1.2253	0.0014937	-0.0011	-0.00034	0.0012	0.00068993

Device Test: 21.3 V_REFCAP(VOLTAGE|VREF/VREF/5/5/0/0/5/100kHz//@V_REFCAP)

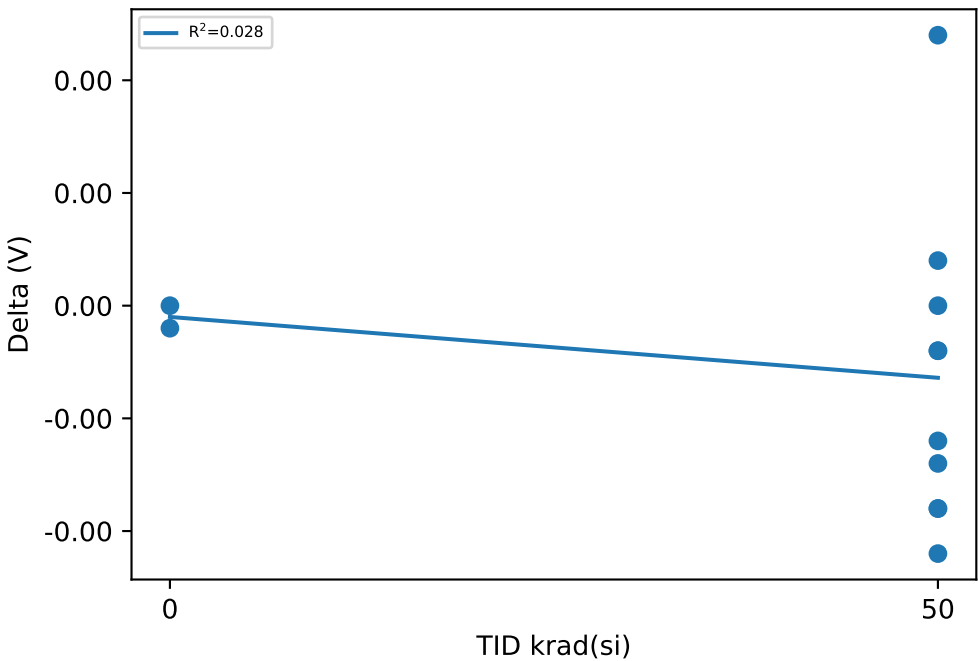
TID vs Result Stats



Test Results (Lower Limit = 1.211, Upper Limit = 1.235 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.2229	1.2228	-0.0001
2	0	Correlation	1.2255	1.2255	0
4	50	Bias	1.2234	1.2223	-0.0011
6	50	Bias	1.2226	1.2217	-0.0009
7	50	Bias	1.2252	1.2252	0
8	50	Bias	1.2238	1.2231	-0.0007
9	50	Bias	1.2257	1.2251	-0.0006
11	50	Unbias	1.2223	1.2225	0.0002
12	50	Unbias	1.2214	1.2212	-0.0002
13	50	Unbias	1.2214	1.2212	-0.0002
14	50	Unbias	1.2221	1.2212	-0.0009
15	50	Unbias	1.2215	1.2227	0.0012

TID vs Post - Pre Exposure Delta

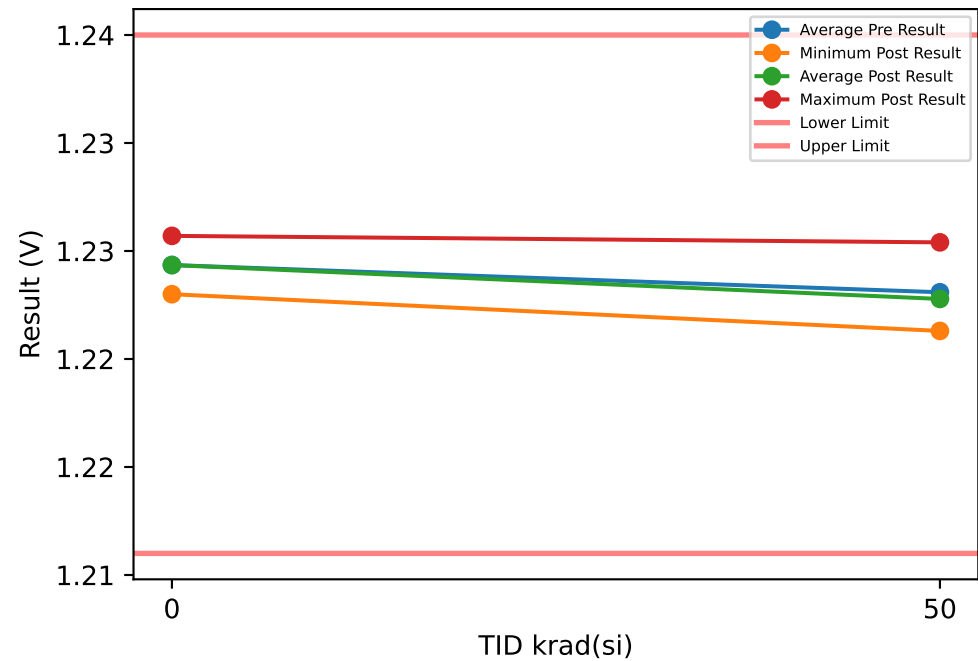


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2229	1.2242	1.2255	0.0018385	1.2228	1.2242	1.2255	0.0019092	-0.0001	-5e-05	0	7.0711e-05
50	1.2214	1.2229	1.2257	0.0015536	1.2212	1.2226	1.2252	0.0014928	-0.0011	-0.00032	0.0012	0.00068443

Device Test: 21.31 V_REFCAP(VOLTAGE|VREF/VREF/14/14/0/1000/5/100kHz//@V_REFCAP)

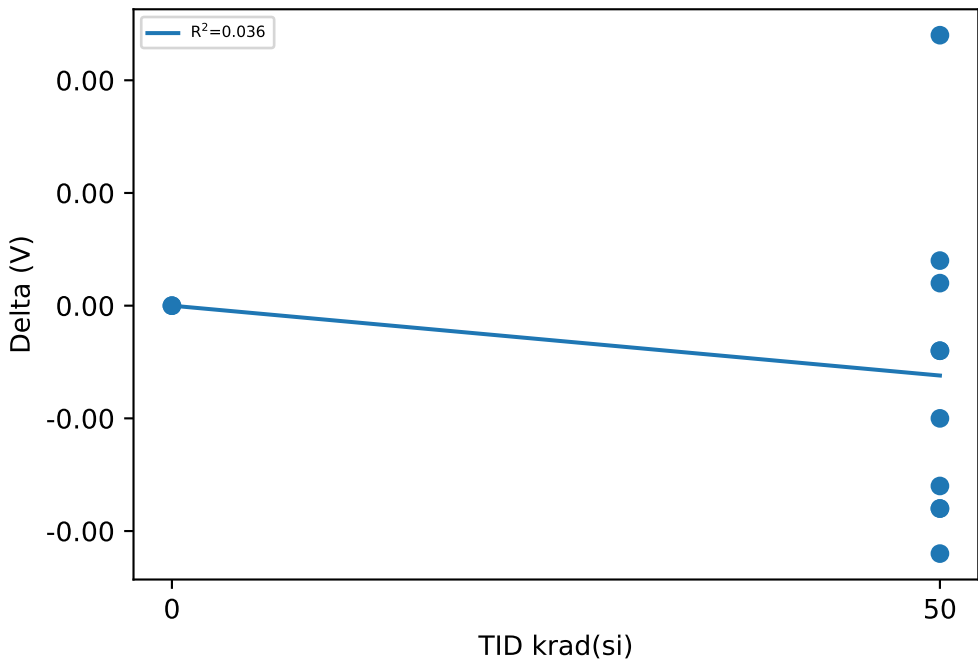
TID vs Result Stats



Test Results (Lower Limit = 1.211, Upper Limit = 1.235 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.223	1.223	0
2	0	Correlation	1.2257	1.2257	0
4	50	Bias	1.2235	1.2224	-0.0011
6	50	Bias	1.2227	1.2218	-0.0009
7	50	Bias	1.2253	1.2254	0.0001
8	50	Bias	1.224	1.2232	-0.0008
9	50	Bias	1.2258	1.2253	-0.0005
11	50	Unbias	1.2225	1.2227	0.0002
12	50	Unbias	1.2216	1.2214	-0.0002
13	50	Unbias	1.2215	1.2213	-0.0002
14	50	Unbias	1.2223	1.2214	-0.0009
15	50	Unbias	1.2217	1.2229	0.0012

TID vs Post - Pre Exposure Delta

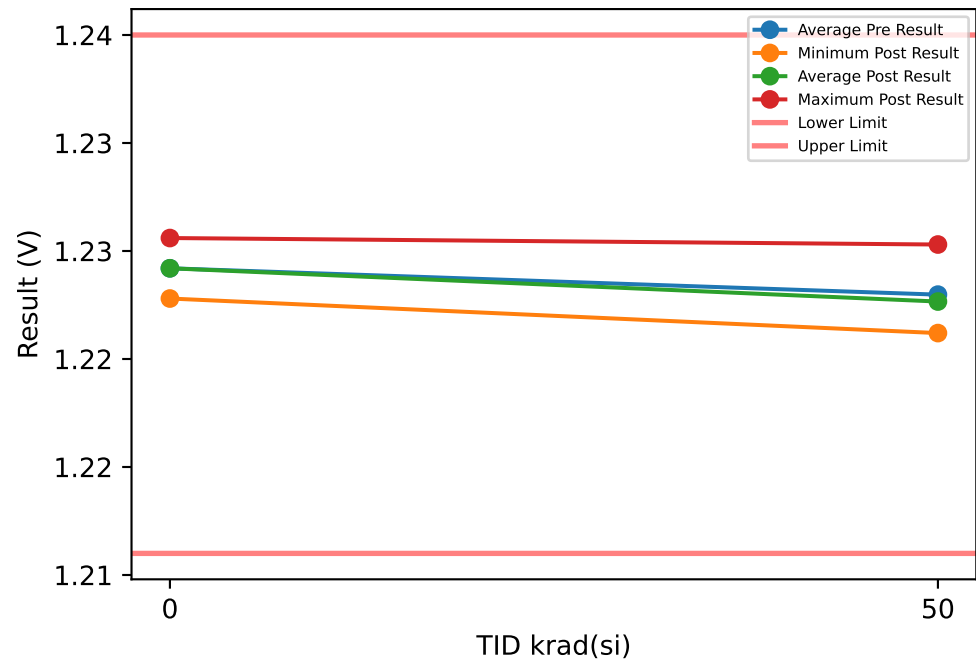


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.223	1.2244	1.2257	0.0019092	1.223	1.2244	1.2257	0.0019092	0	0	0	0
50	1.2215	1.2231	1.2258	0.0015286	1.2213	1.2228	1.2254	0.0015098	-0.0011	-0.00031	0.0012	0.00069354

Device Test: 21.33 V_REFCAP(VOLTAGE|VREF/VREF/4.5/4.5/0/1000/4.5/500kHz//@V_REFCAP)

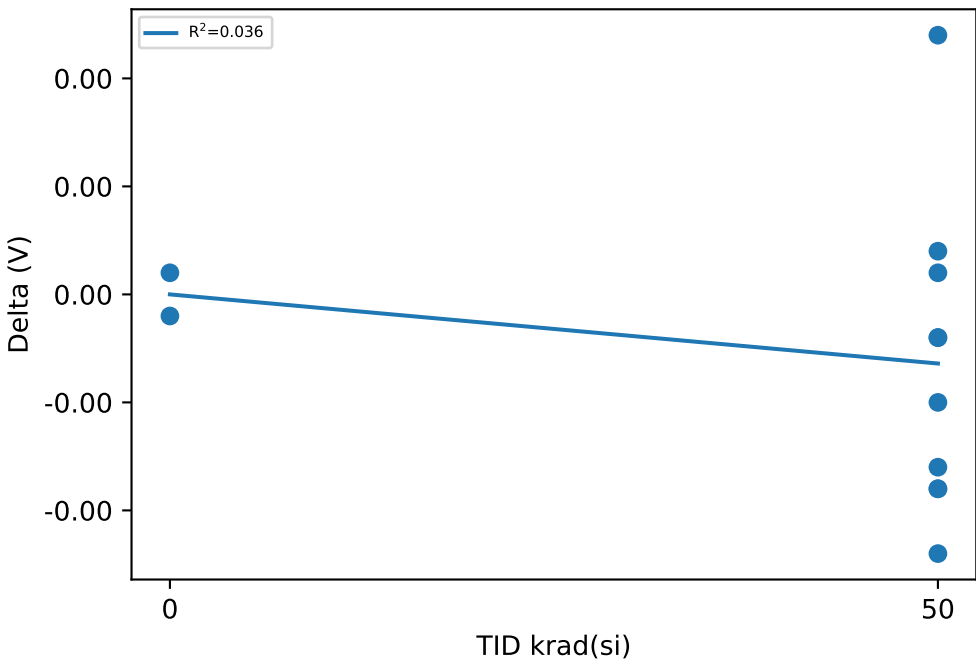
TID vs Result Stats



Test Results (Lower Limit = 1.211, Upper Limit = 1.235 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.2229	1.2228	-0.0001
2	0	Correlation	1.2255	1.2256	0.0001
4	50	Bias	1.2235	1.2223	-0.0012
6	50	Bias	1.2226	1.2217	-0.0009
7	50	Bias	1.2252	1.2253	0.0001
8	50	Bias	1.2239	1.2231	-0.0008
9	50	Bias	1.2257	1.2252	-0.0005
11	50	Unbias	1.2223	1.2225	0.0002
12	50	Unbias	1.2215	1.2213	-0.0002
13	50	Unbias	1.2214	1.2212	-0.0002
14	50	Unbias	1.2221	1.2212	-0.0009
15	50	Unbias	1.2216	1.2228	0.0012

TID vs Post - Pre Exposure Delta

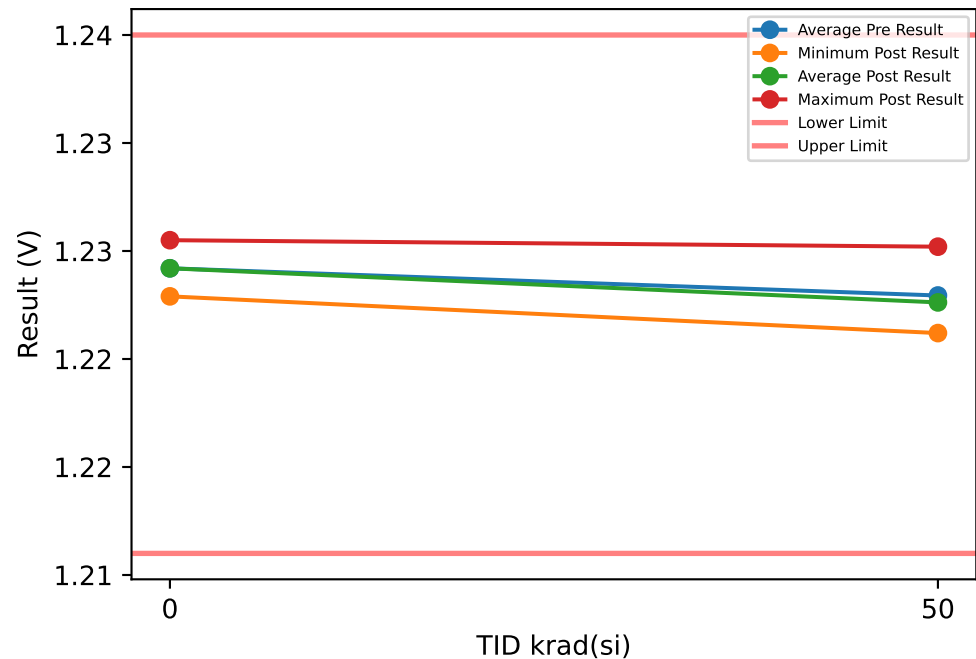


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2229	1.2242	1.2255	0.0018385	1.2228	1.2242	1.2256	0.0019799	-0.0001	0	0.0001	0.00014142
50	1.2214	1.223	1.2257	0.0015426	1.2212	1.2227	1.2253	0.0015211	-0.0012	-0.00032	0.0012	0.00070679

Device Test: 21.35 V_REFCAP(VOLTAGE|VREF/VREF/5/5/0/1000/5/500kHz//@V_REFCAP)

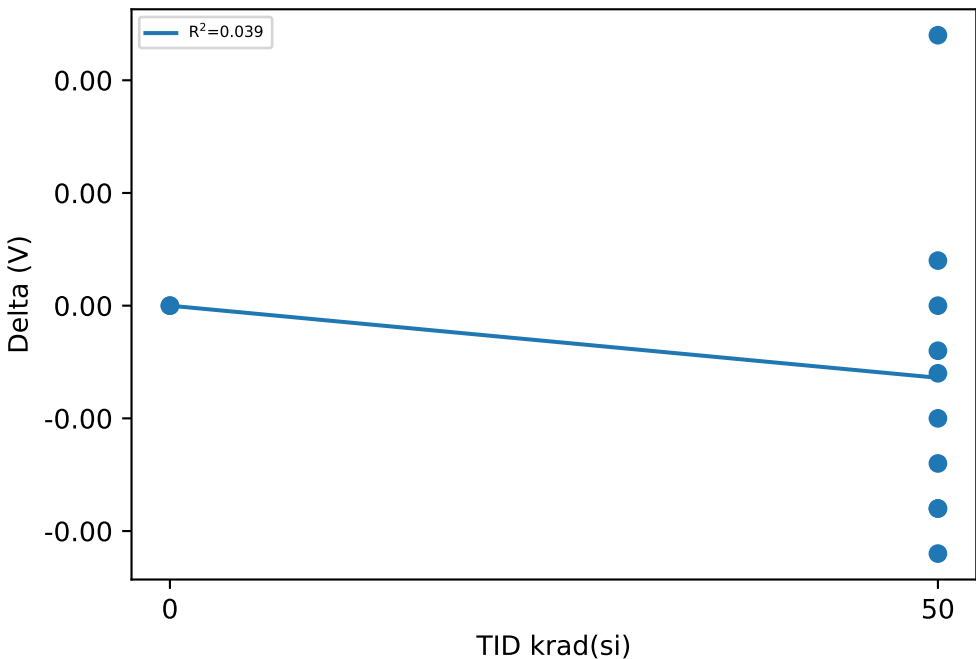
TID vs Result Stats



Test Results (Lower Limit = 1.211, Upper Limit = 1.235 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.2229	1.2229	0
2	0	Correlation	1.2255	1.2255	0
4	50	Bias	1.2234	1.2223	-0.0011
6	50	Bias	1.2226	1.2217	-0.0009
7	50	Bias	1.2252	1.2252	0
8	50	Bias	1.2238	1.2231	-0.0007
9	50	Bias	1.2256	1.2251	-0.0005
11	50	Unbias	1.2223	1.2225	0.0002
12	50	Unbias	1.2215	1.2212	-0.0003
13	50	Unbias	1.2214	1.2212	-0.0002
14	50	Unbias	1.2221	1.2212	-0.0009
15	50	Unbias	1.2215	1.2227	0.0012

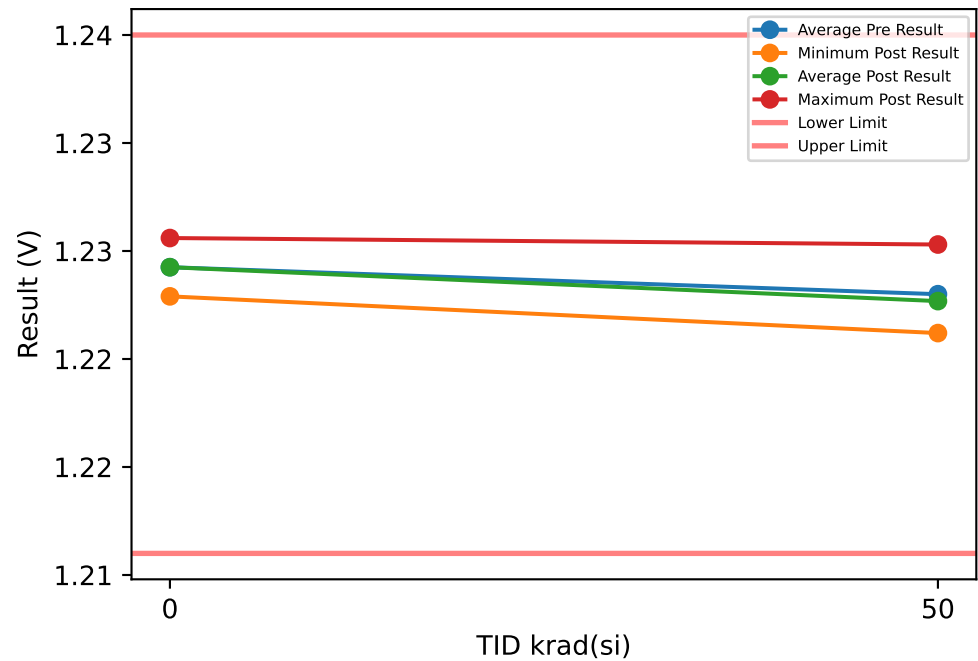
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2229	1.2242	1.2255	0.0018385	1.2229	1.2242	1.2255	0.0018385	0	0	0	0
50	1.2214	1.2229	1.2256	0.0015233	1.2212	1.2226	1.2252	0.0014928	-0.0011	-0.00032	0.0012	0.00067954

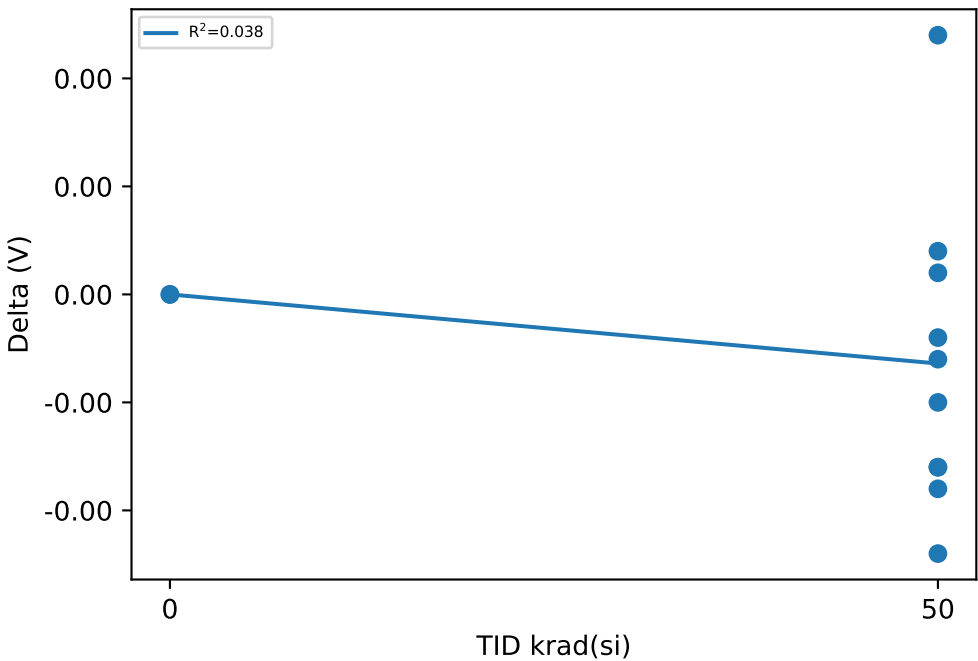
TID vs Result Stats



Test Results (Lower Limit = 1.211, Upper Limit = 1.235 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.2229	1.2229	0
2	0	Correlation	1.2256	1.2256	0
4	50	Bias	1.2235	1.2223	-0.0012
6	50	Bias	1.2226	1.2218	-0.0008
7	50	Bias	1.2252	1.2253	0.0001
8	50	Bias	1.2239	1.2231	-0.0008
9	50	Bias	1.2257	1.2252	-0.0005
11	50	Unbias	1.2224	1.2226	0.0002
12	50	Unbias	1.2215	1.2212	-0.0003
13	50	Unbias	1.2214	1.2212	-0.0002
14	50	Unbias	1.2222	1.2213	-0.0009
15	50	Unbias	1.2216	1.2228	0.0012

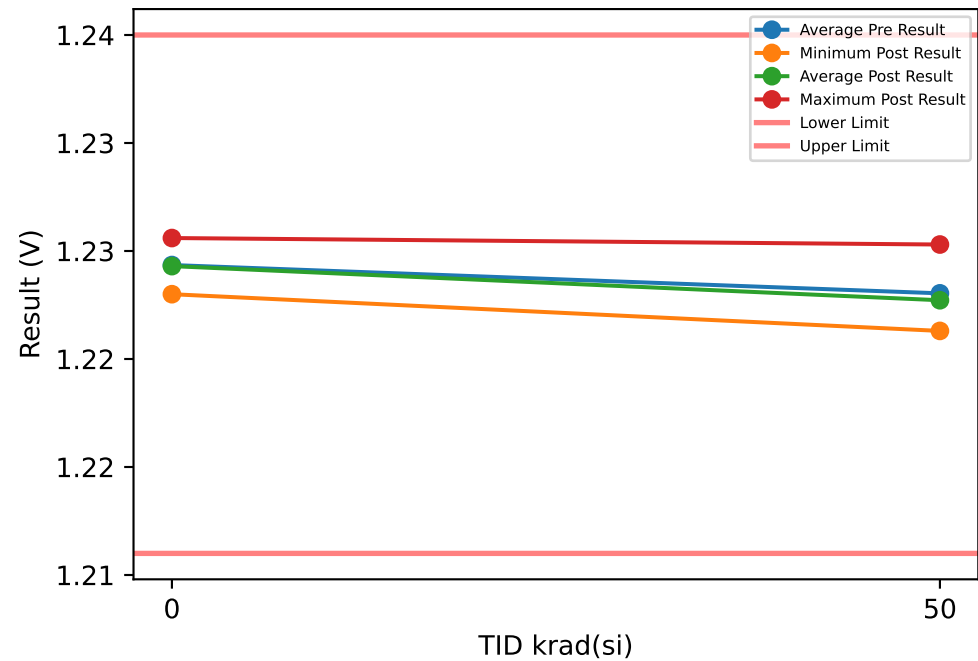
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2229	1.2243	1.2256	0.0019092	1.2229	1.2243	1.2256	0.0019092	0	0	0	0
50	1.2214	1.223	1.2257	0.0015319	1.2212	1.2227	1.2253	0.0015135	-0.0012	-0.00032	0.0012	0.0006973

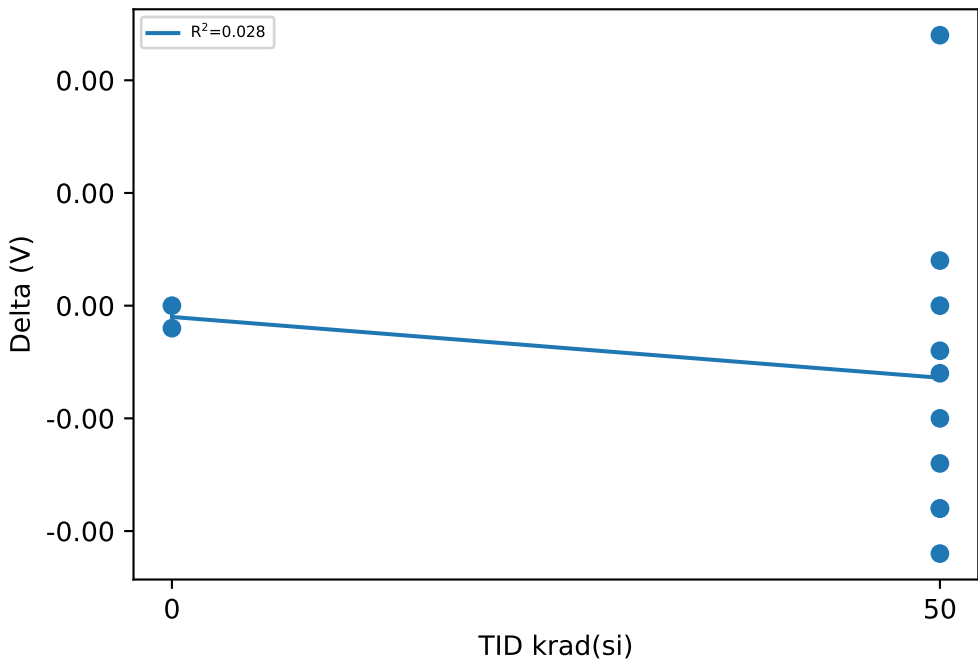
TID vs Result Stats



Test Results (Lower Limit = 1.211, Upper Limit = 1.235 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.223	1.223	0
2	0	Correlation	1.2257	1.2256	-0.0001
4	50	Bias	1.2235	1.2224	-0.0011
6	50	Bias	1.2227	1.2218	-0.0009
7	50	Bias	1.2253	1.2253	0
8	50	Bias	1.2239	1.2232	-0.0007
9	50	Bias	1.2257	1.2252	-0.0005
11	50	Unbias	1.2224	1.2226	0.0002
12	50	Unbias	1.2216	1.2213	-0.0003
13	50	Unbias	1.2215	1.2213	-0.0002
14	50	Unbias	1.2222	1.2213	-0.0009
15	50	Unbias	1.2216	1.2228	0.0012

TID vs Post - Pre Exposure Delta

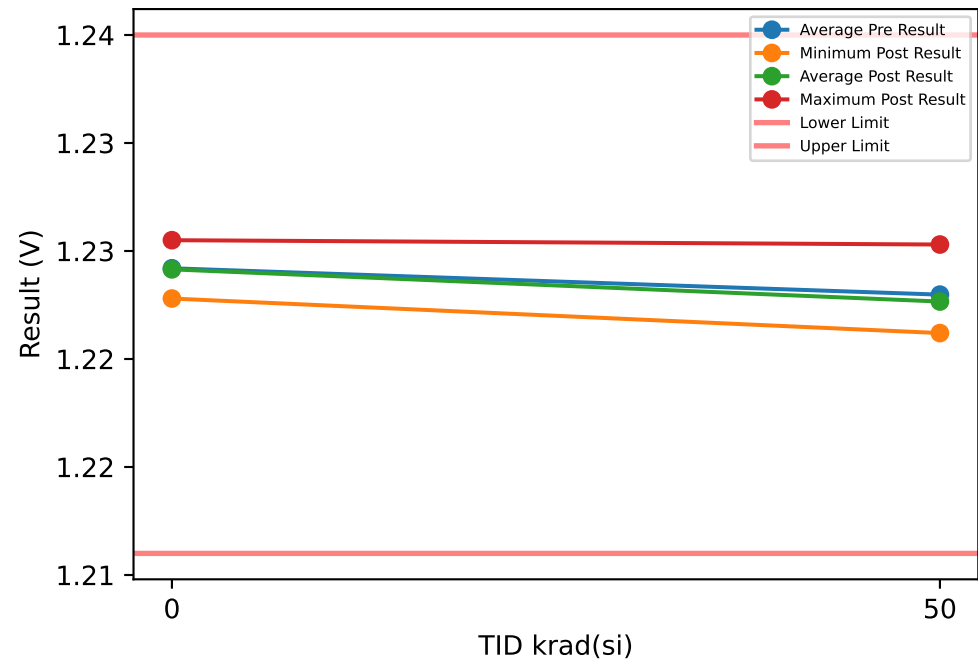


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.223	1.2244	1.2257	0.0019092	1.223	1.2243	1.2256	0.0018385	-0.0001	-5e-05	0	7.0711e-05
50	1.2215	1.223	1.2257	0.0015233	1.2213	1.2227	1.2253	0.0014928	-0.0011	-0.00032	0.0012	0.00067954

Device Test: 21.41 V_REFCAP(VOLTAGE|VREF/VREF/4.5/4.5/0/1000/4.5/1MHz//@V_REFCAP)

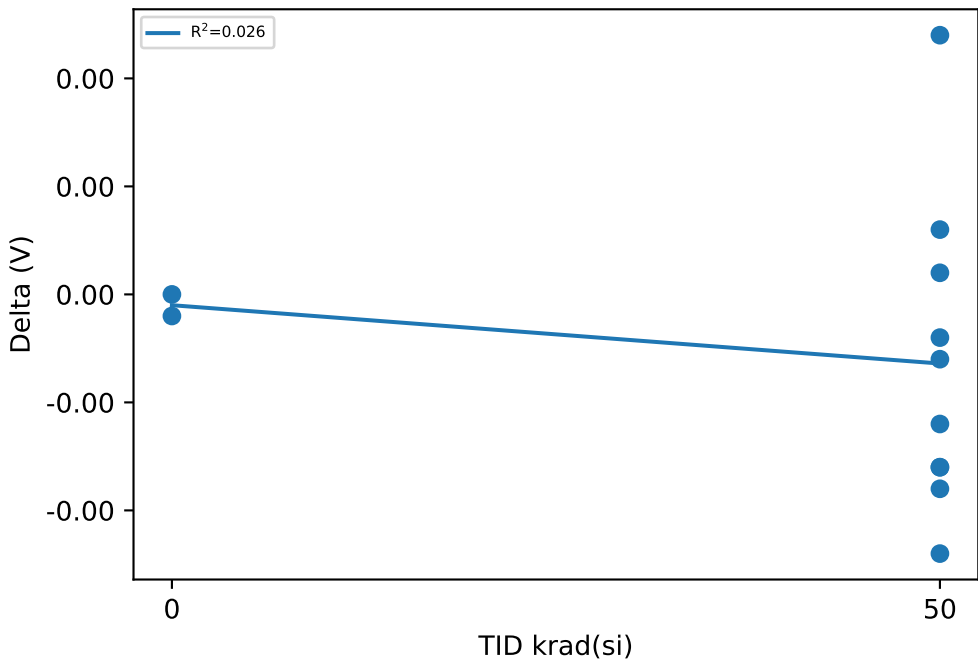
TID vs Result Stats



Test Results (Lower Limit = 1.211, Upper Limit = 1.235 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.2229	1.2228	-0.0001
2	0	Correlation	1.2255	1.2255	0
4	50	Bias	1.2235	1.2223	-0.0012
6	50	Bias	1.2226	1.2217	-0.0009
7	50	Bias	1.2252	1.2253	0.0001
8	50	Bias	1.2239	1.2231	-0.0008
9	50	Bias	1.2257	1.2251	-0.0006
11	50	Unbias	1.2223	1.2226	0.0003
12	50	Unbias	1.2215	1.2212	-0.0003
13	50	Unbias	1.2214	1.2212	-0.0002
14	50	Unbias	1.2221	1.2213	-0.0008
15	50	Unbias	1.2216	1.2228	0.0012

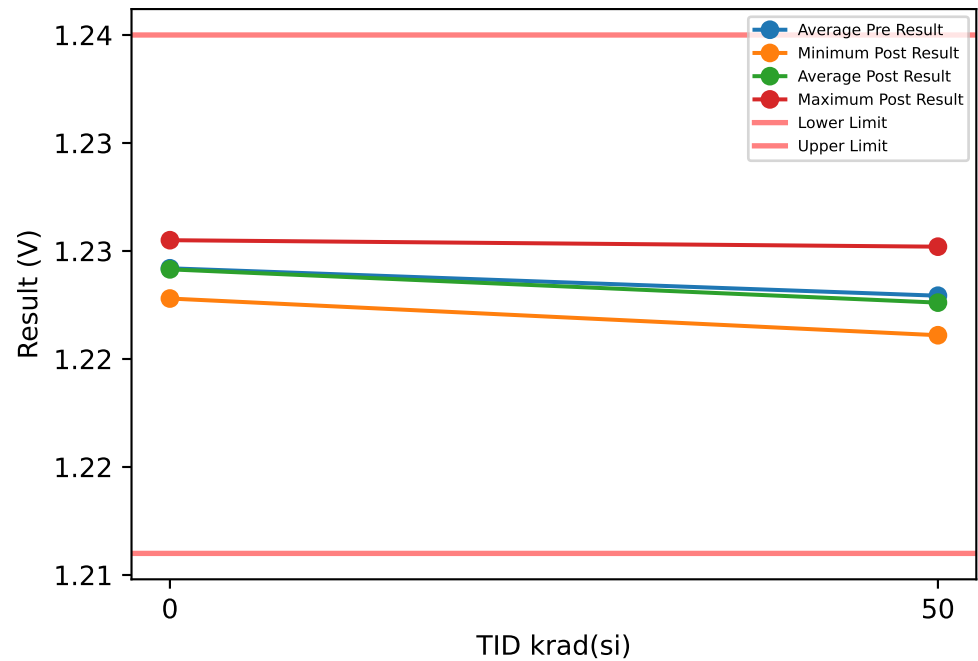
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2229	1.2242	1.2255	0.0018385	1.2228	1.2242	1.2255	0.0019092	-0.0001	-5e-05	0	7.0711e-05
50	1.2214	1.223	1.2257	0.0015426	1.2212	1.2227	1.2253	0.001502	-0.0012	-0.00032	0.0012	0.00070993

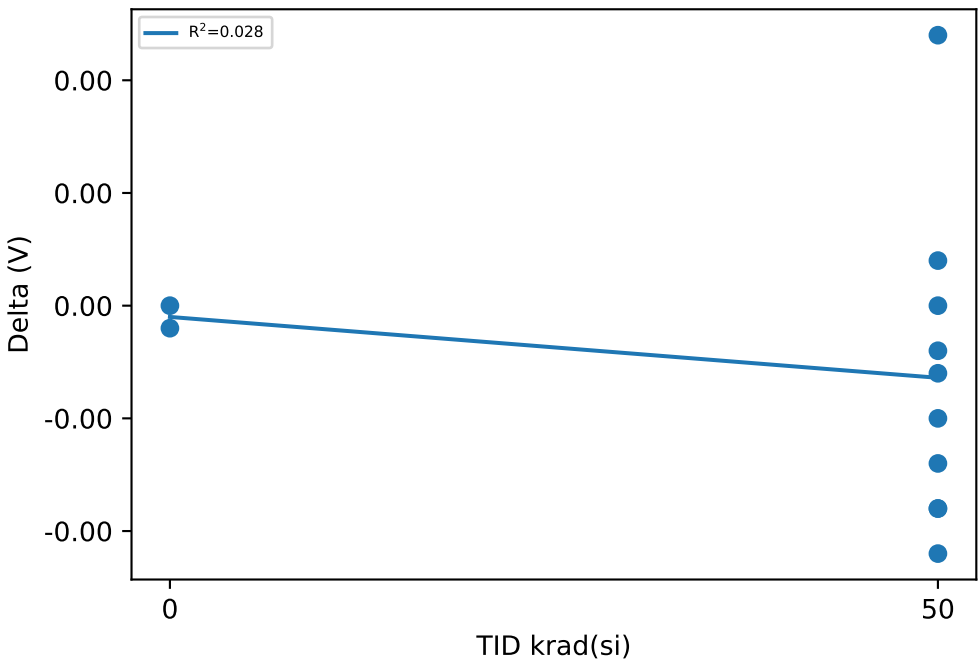
TID vs Result Stats



Test Results (Lower Limit = 1.211, Upper Limit = 1.235 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.2229	1.2228	-0.0001
2	0	Correlation	1.2255	1.2255	0
4	50	Bias	1.2234	1.2223	-0.0011
6	50	Bias	1.2226	1.2217	-0.0009
7	50	Bias	1.2252	1.2252	0
8	50	Bias	1.2238	1.2231	-0.0007
9	50	Bias	1.2256	1.2251	-0.0005
11	50	Unbias	1.2223	1.2225	0.0002
12	50	Unbias	1.2214	1.2212	-0.0002
13	50	Unbias	1.2214	1.2211	-0.0003
14	50	Unbias	1.2221	1.2212	-0.0009
15	50	Unbias	1.2215	1.2227	0.0012

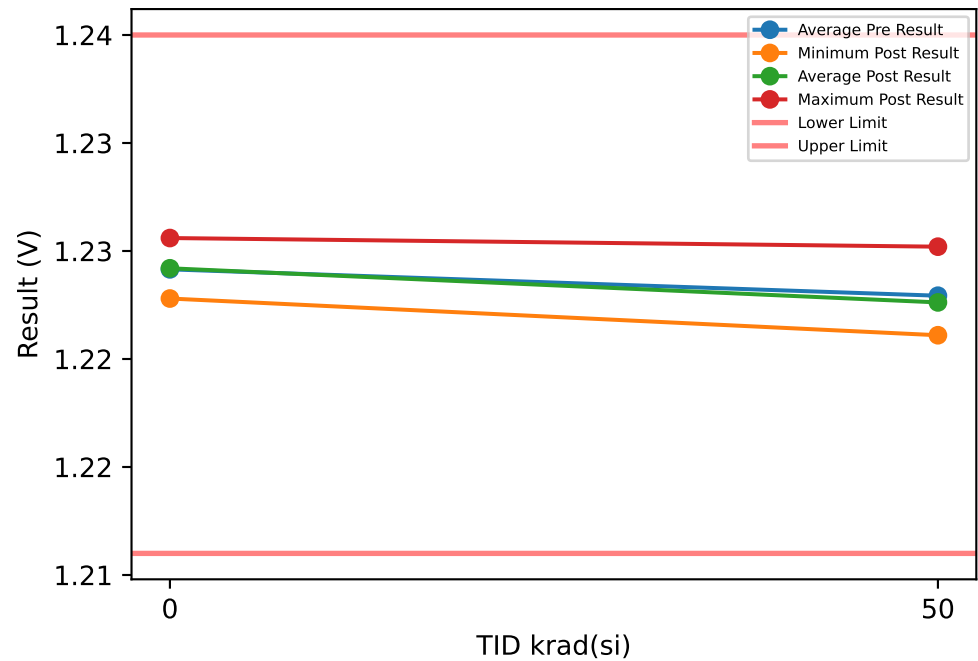
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2229	1.2242	1.2255	0.0018385	1.2228	1.2242	1.2255	0.0019092	-0.0001	-5e-05	0	7.0711e-05
50	1.2214	1.2229	1.2256	0.0015341	1.2211	1.2226	1.2252	0.0015037	-0.0011	-0.00032	0.0012	0.00067954

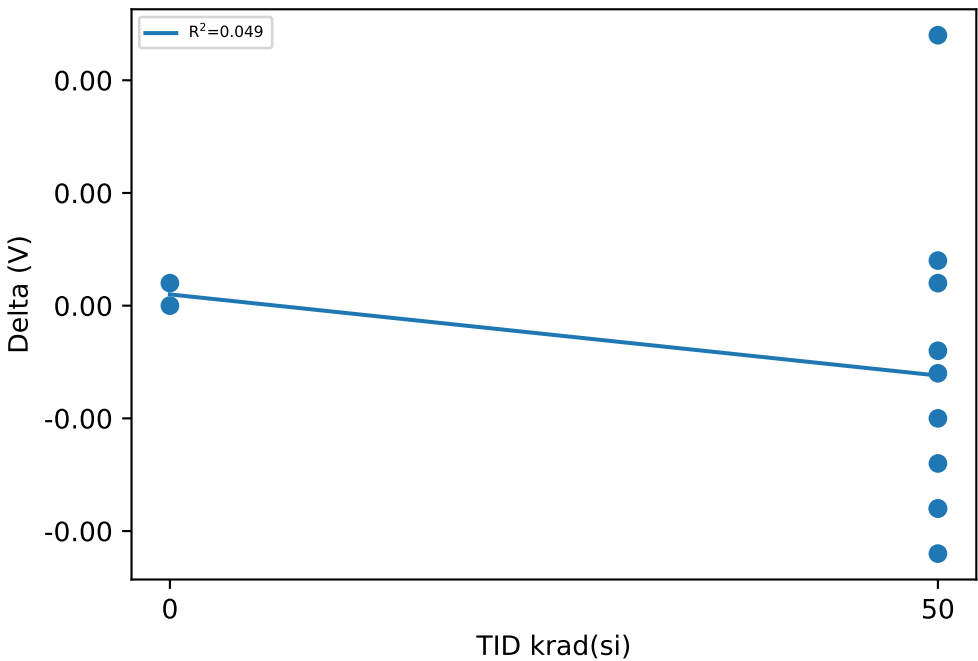
TID vs Result Stats



Test Results (Lower Limit = 1.211, Upper Limit = 1.235 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.2228	1.2228	0
2	0	Correlation	1.2255	1.2256	0.0001
4	50	Bias	1.2234	1.2223	-0.0011
6	50	Bias	1.2226	1.2217	-0.0009
7	50	Bias	1.2251	1.2252	0.0001
8	50	Bias	1.2238	1.2231	-0.0007
9	50	Bias	1.2257	1.2252	-0.0005
11	50	Unbias	1.2223	1.2225	0.0002
12	50	Unbias	1.2214	1.2212	-0.0002
13	50	Unbias	1.2214	1.2211	-0.0003
14	50	Unbias	1.2221	1.2212	-0.0009
15	50	Unbias	1.2215	1.2227	0.0012

TID vs Post - Pre Exposure Delta

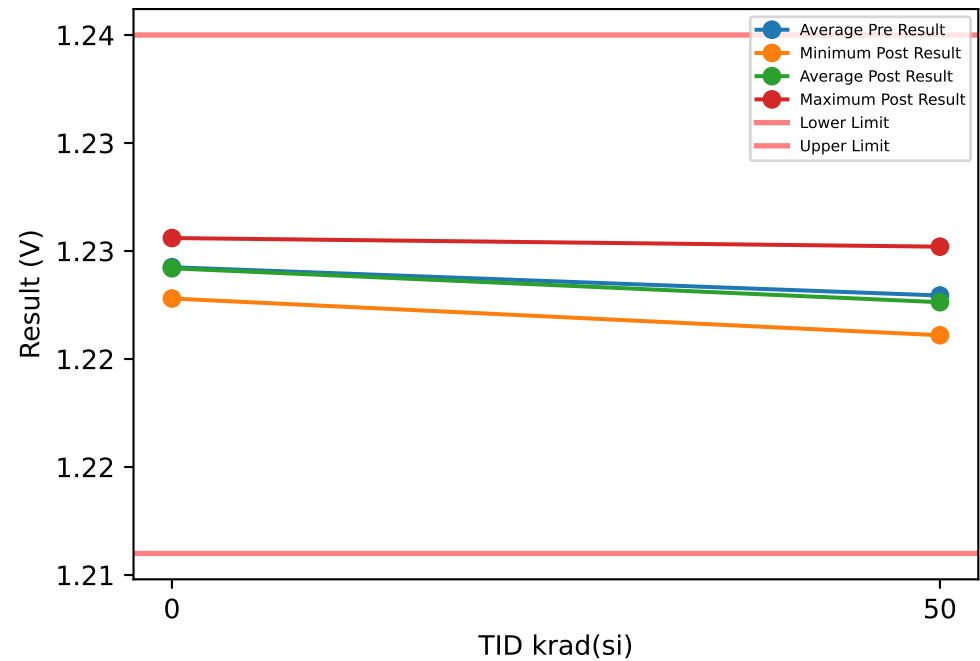


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2228	1.2242	1.2255	0.0019092	1.2228	1.2242	1.2256	0.0019799	0	5e-05	0.0001	7.0711e-05
50	1.2214	1.2229	1.2257	0.0015377	1.2211	1.2226	1.2252	0.0015223	-0.0011	-0.00031	0.0012	0.00068548

Device Test: 21.47 V_REFCAP(VOLTAGE|VREF/VREF/14/14/0/1000/5/1MHz//@V_REFCAP)

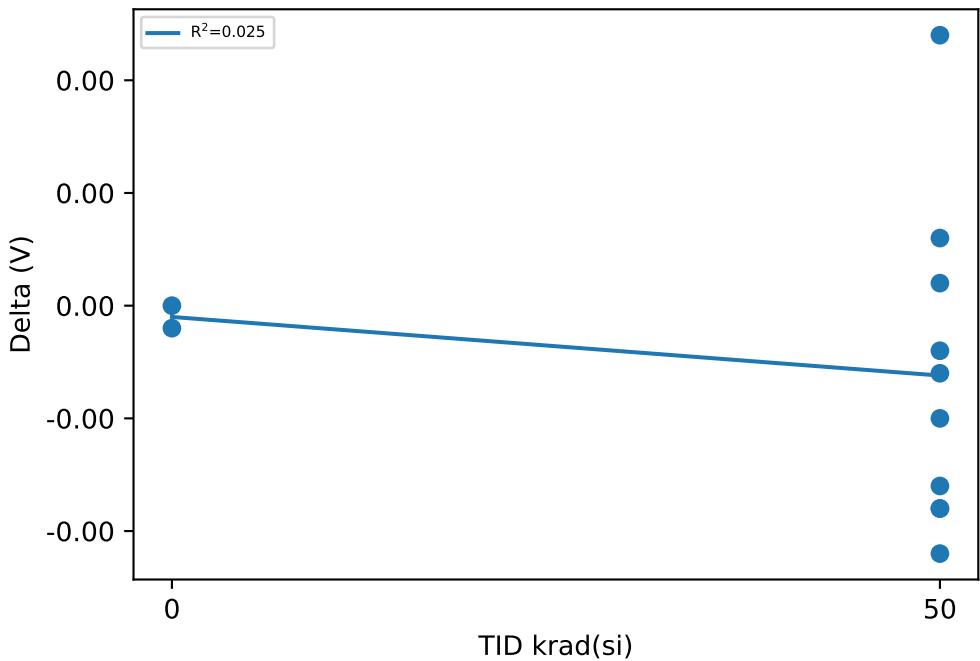
TID vs Result Stats



Test Results (Lower Limit = 1.211, Upper Limit = 1.235 (V))

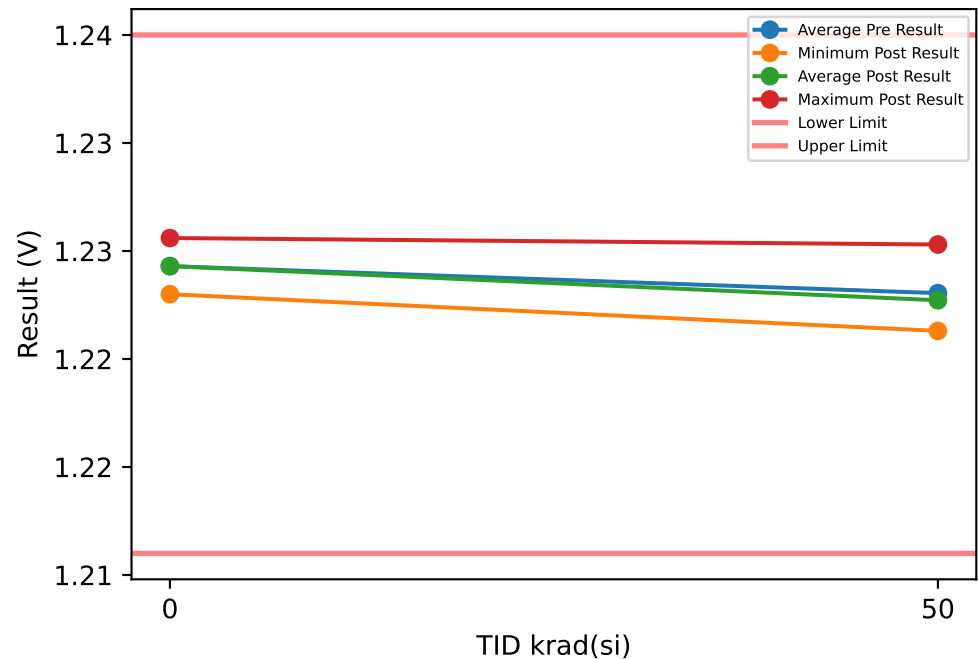
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.2229	1.2228	-0.0001
2	0	Correlation	1.2256	1.2256	0
4	50	Bias	1.2234	1.2223	-0.0011
6	50	Bias	1.2226	1.2217	-0.0009
7	50	Bias	1.2251	1.2252	0.0001
8	50	Bias	1.2239	1.2231	-0.0008
9	50	Bias	1.2257	1.2252	-0.0005
11	50	Unbias	1.2223	1.2226	0.0003
12	50	Unbias	1.2215	1.2212	-0.0003
13	50	Unbias	1.2213	1.2211	-0.0002
14	50	Unbias	1.2221	1.2212	-0.0009
15	50	Unbias	1.2215	1.2227	0.0012

TID vs Post - Pre Exposure Delta



Device Test: 21.5 V_REFCAP(VOLTAGE|VREF/VREF/12/12/0/0/5/100kHz//@V_REFCAP)

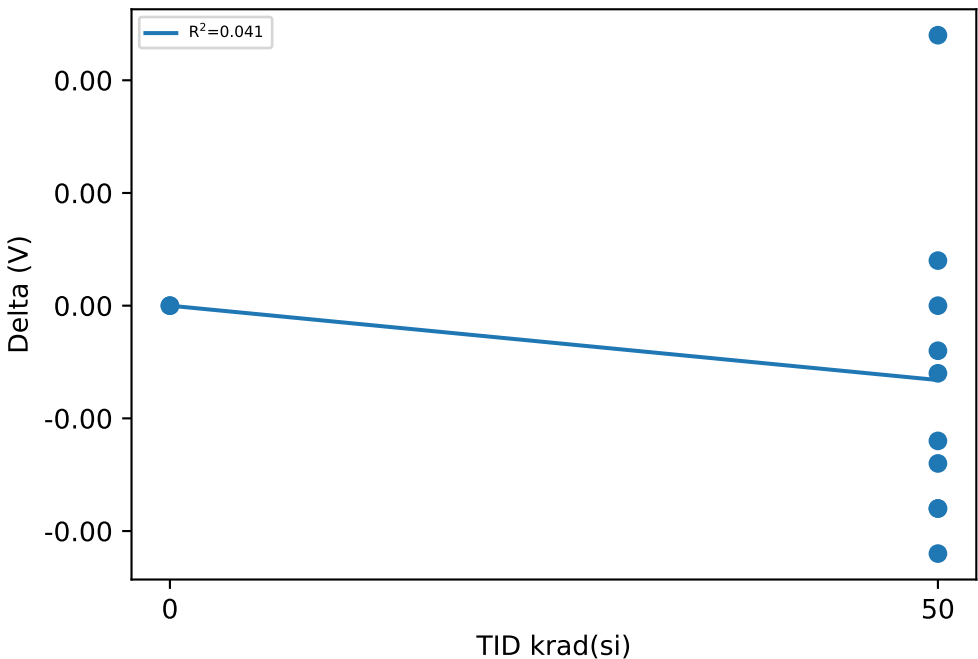
TID vs Result Stats



Test Results (Lower Limit = 1.211, Upper Limit = 1.235 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.223	1.223	0
2	0	Correlation	1.2256	1.2256	0
4	50	Bias	1.2235	1.2224	-0.0011
6	50	Bias	1.2227	1.2218	-0.0009
7	50	Bias	1.2253	1.2253	0
8	50	Bias	1.2239	1.2232	-0.0007
9	50	Bias	1.2258	1.2252	-0.0006
11	50	Unbias	1.2224	1.2226	0.0002
12	50	Unbias	1.2216	1.2213	-0.0003
13	50	Unbias	1.2215	1.2213	-0.0002
14	50	Unbias	1.2222	1.2213	-0.0009
15	50	Unbias	1.2216	1.2228	0.0012

TID vs Post - Pre Exposure Delta

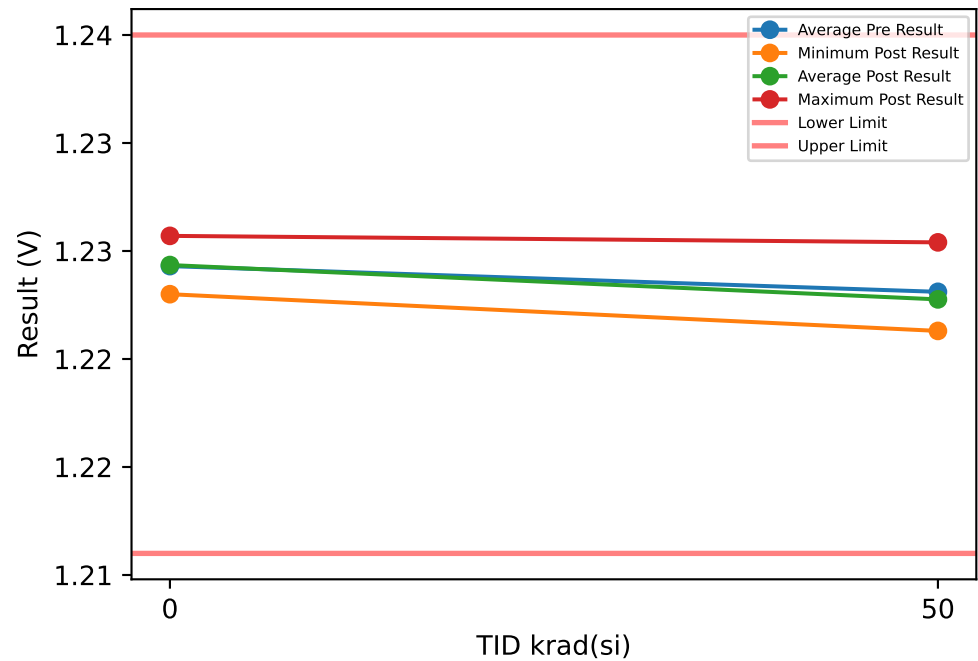


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.223	1.2243	1.2256	0.0018385	1.223	1.2243	1.2256	0.0018385	0	0	0	0
50	1.2215	1.223	1.2258	0.0015429	1.2213	1.2227	1.2253	0.0014928	-0.0011	-0.00033	0.0012	0.00068321

Device Test: 21.7 V_REFCAP(VOLTAGE|VREF/VREF/14/14/0/0/5/100kHz//@V_REFCAP)

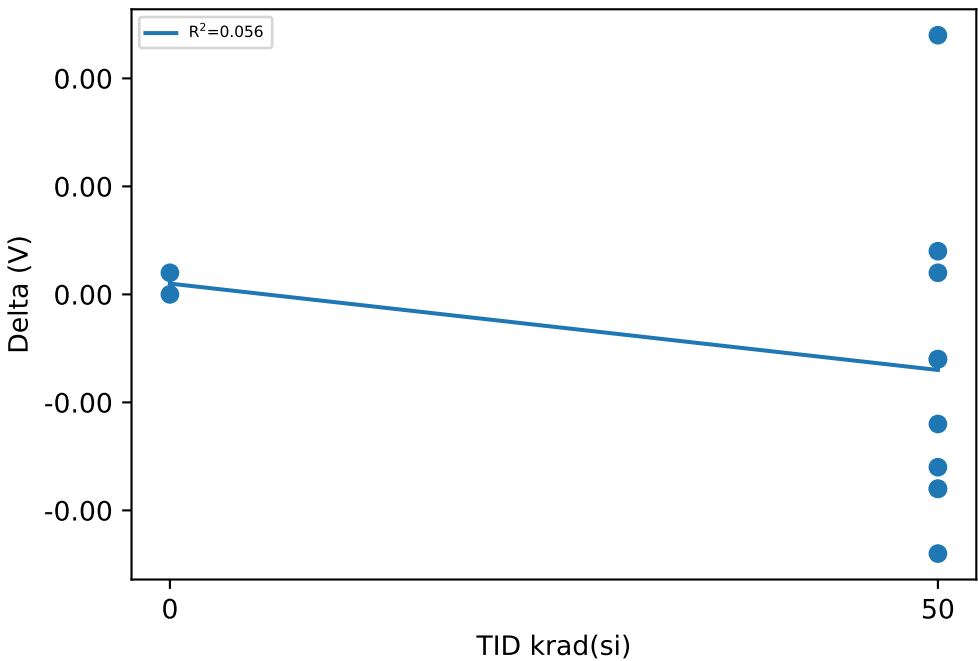
TID vs Result Stats



Test Results (Lower Limit = 1.211, Upper Limit = 1.235 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.223	1.223	0
2	0	Correlation	1.2256	1.2257	0.0001
4	50	Bias	1.2236	1.2224	-0.0012
6	50	Bias	1.2227	1.2218	-0.0009
7	50	Bias	1.2253	1.2254	0.0001
8	50	Bias	1.224	1.2232	-0.0008
9	50	Bias	1.2258	1.2252	-0.0006
11	50	Unbias	1.2225	1.2227	0.0002
12	50	Unbias	1.2216	1.2213	-0.0003
13	50	Unbias	1.2216	1.2213	-0.0003
14	50	Unbias	1.2223	1.2214	-0.0009
15	50	Unbias	1.2217	1.2229	0.0012

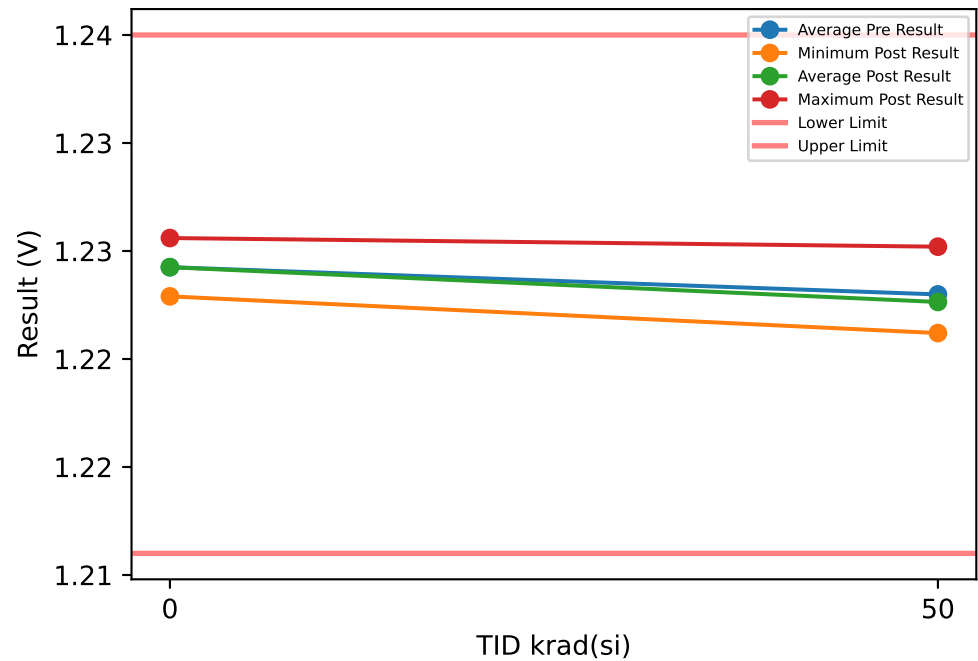
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.223	1.2243	1.2256	0.0018385	1.223	1.2244	1.2257	0.0019092	0	5e-05	0.0001	7.0711e-05
50	1.2216	1.2231	1.2258	0.0015206	1.2213	1.2228	1.2254	0.001502	-0.0012	-0.00035	0.0012	0.0007075

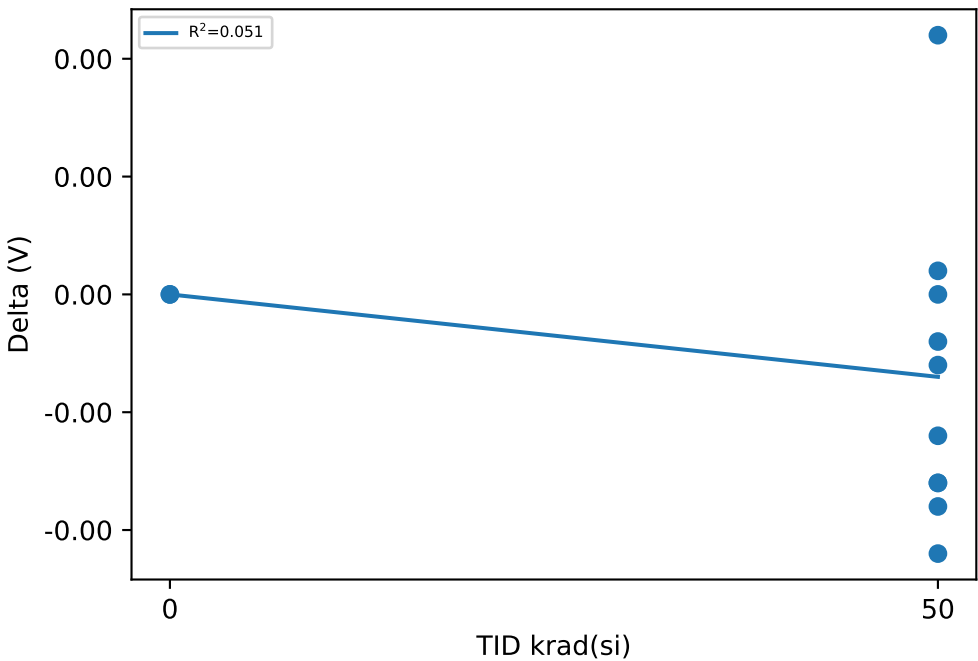
TID vs Result Stats



Test Results (Lower Limit = 1.211, Upper Limit = 1.235 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.2229	1.2229	0
2	0	Correlation	1.2256	1.2256	0
4	50	Bias	1.2234	1.2223	-0.0011
6	50	Bias	1.2226	1.2218	-0.0008
7	50	Bias	1.2252	1.2252	0
8	50	Bias	1.2239	1.2231	-0.0008
9	50	Bias	1.2257	1.2251	-0.0006
11	50	Unbias	1.2224	1.2225	0.0001
12	50	Unbias	1.2215	1.2212	-0.0003
13	50	Unbias	1.2214	1.2212	-0.0002
14	50	Unbias	1.2222	1.2213	-0.0009
15	50	Unbias	1.2216	1.2227	0.0011

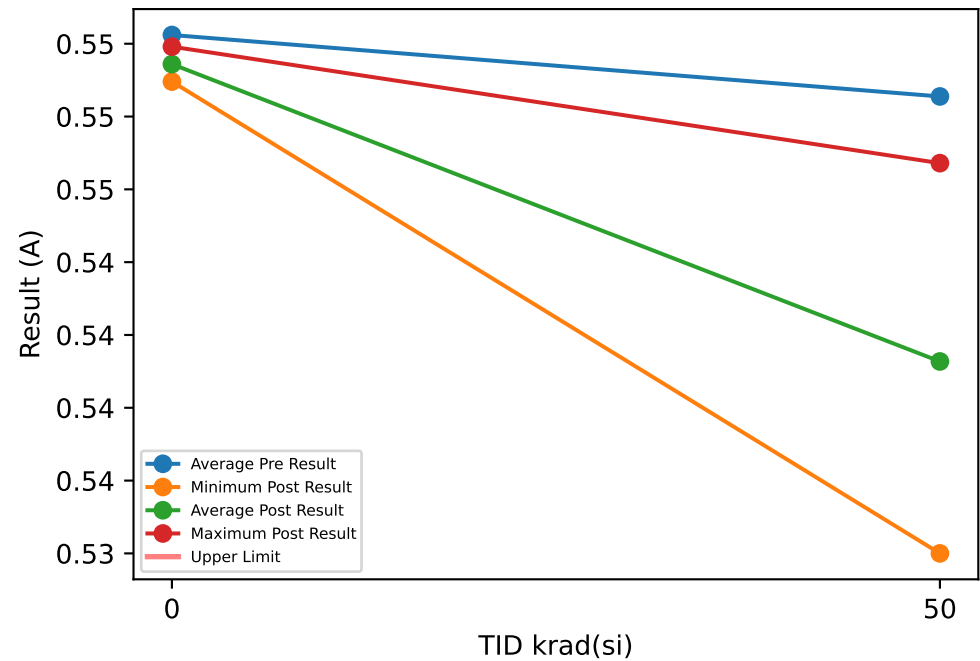
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2229	1.2243	1.2256	0.0019092	1.2229	1.2243	1.2256	0.0019092	0	0	0	0
50	1.2214	1.223	1.2257	0.0015286	1.2212	1.2226	1.2252	0.0014759	-0.0011	-0.00035	0.0011	0.0006485

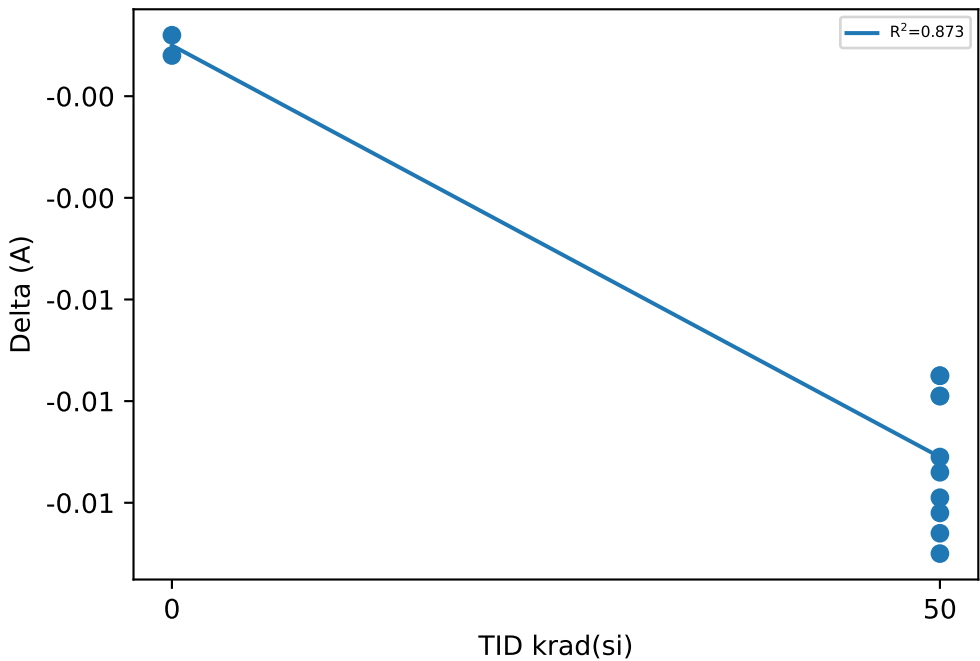
TID vs Result Stats



Test Results (No Limits Specified (A))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.5524	0.5512	-0.0012
2	0	Correlation	0.5532	0.5524	-0.0008
4	50	Bias	0.5469	0.5378	-0.0091
6	50	Bias	0.5469	0.5394	-0.0075
7	50	Bias	0.5465	0.539	-0.0075
8	50	Bias	0.5469	0.539	-0.0079
9	50	Bias	0.5429	0.535	-0.0079
11	50	Unbias	0.5567	0.5465	-0.0102
12	50	Unbias	0.5583	0.5484	-0.0099
13	50	Unbias	0.5575	0.5469	-0.0106
14	50	Unbias	0.5484	0.5374	-0.011
15	50	Unbias	0.5559	0.5465	-0.0094

TID vs Post - Pre Exposure Delta

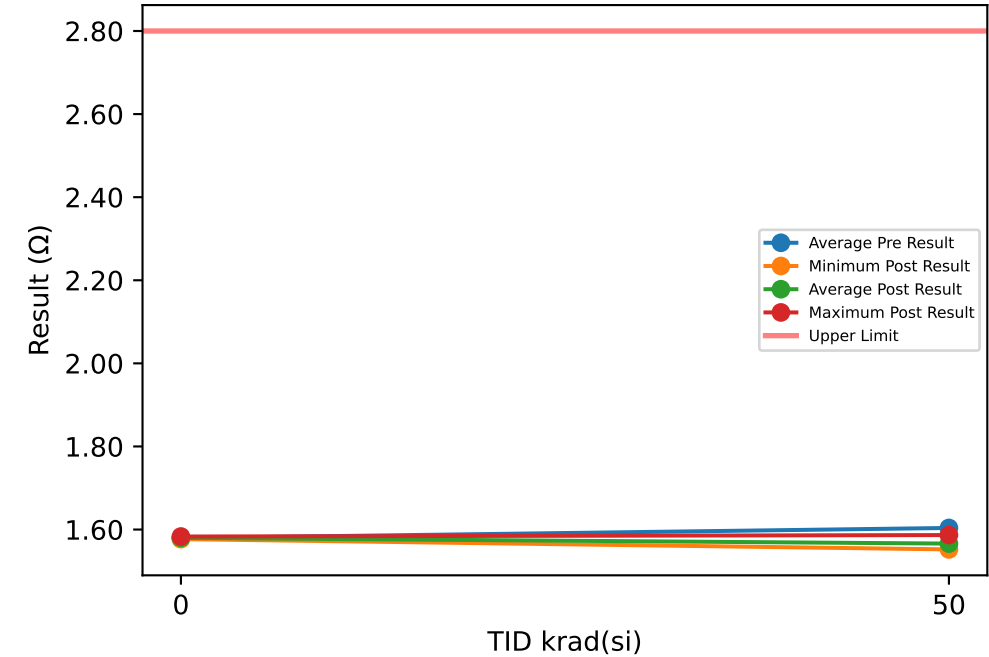


Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5524	0.5528	0.5532	0.00056569	0.5512	0.5518	0.5524	0.00084853	-0.0012	-0.001	-0.0008	0.00028284
50	0.5429	0.55069	0.5583	0.0057167	0.535	0.54159	0.5484	0.0049029	-0.011	-0.0091	-0.0075	0.001325

Device Test: 23.10 ROL(LEVEL|LS_RDSON/OUTL/12/12/100/0/5/500kHz//@ROL)

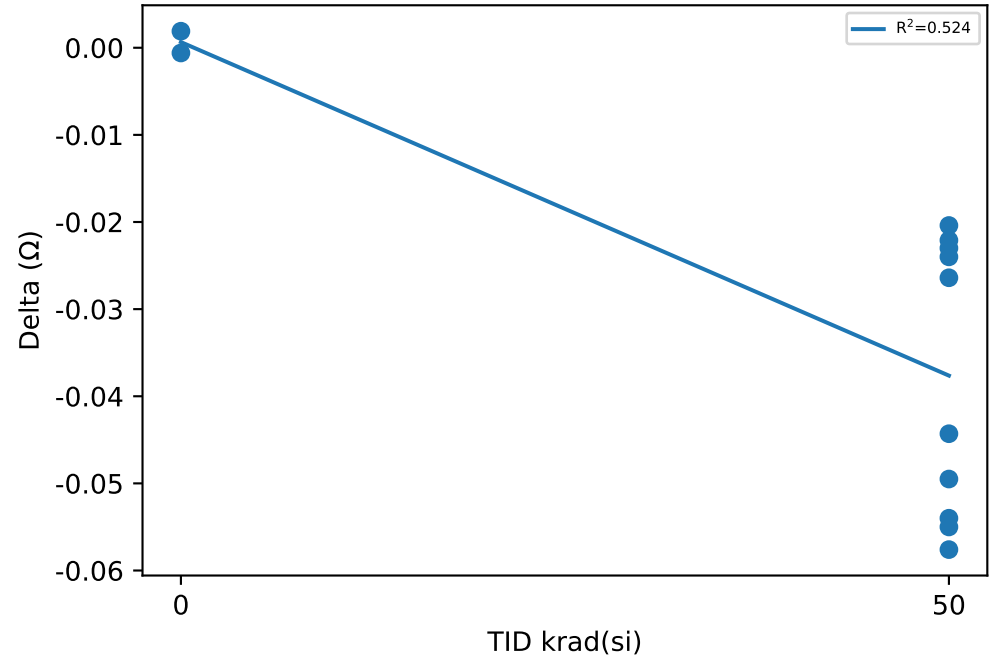
TID vs Result Stats



Test Results (Upper Limit = 2.8 (Ω))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.575	1.5769	0.0019
2	0	Correlation	1.5838	1.5832	-0.0006
4	50	Bias	1.6231	1.5681	-0.055
6	50	Bias	1.5991	1.5548	-0.0443
7	50	Bias	1.6062	1.5522	-0.054
8	50	Bias	1.6151	1.5575	-0.0576
9	50	Bias	1.6122	1.5627	-0.0495
11	50	Unbias	1.5912	1.5682	-0.023
12	50	Unbias	1.5877	1.5673	-0.0204
13	50	Unbias	1.5849	1.5628	-0.0221
14	50	Unbias	1.6078	1.5814	-0.0264
15	50	Unbias	1.6107	1.5867	-0.024

TID vs Post - Pre Exposure Delta

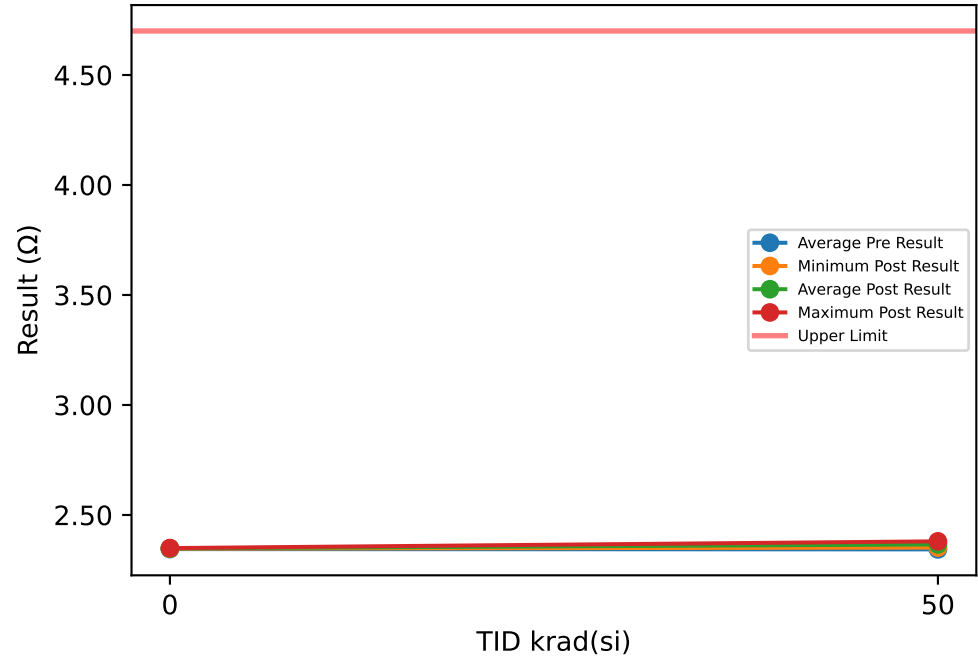


Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.575	1.5794	1.5838	0.0062225	1.5769	1.58	1.5832	0.0044548	-0.0006	0.00065	0.0019	0.0017678
50	1.5849	1.6038	1.6231	0.012638	1.5522	1.5662	1.5867	0.010983	-0.0576	-0.03763	-0.0204	0.015698

Device Test: 23.11 ROH(LEVEL|HS_RDSON/OUTH/14/14/100/0/5/500kHz//@ROH)

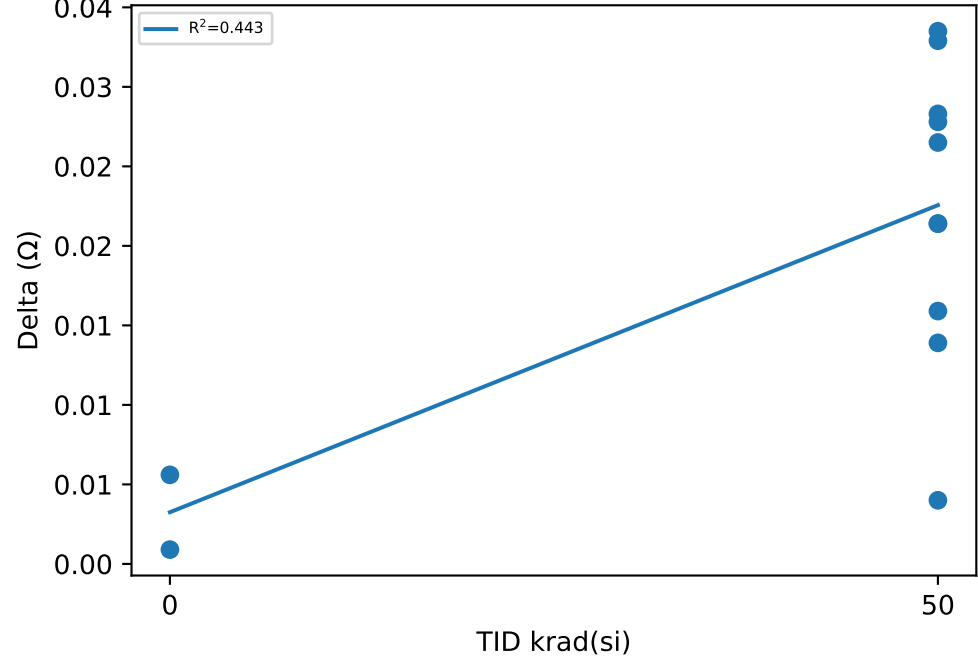
TID vs Result Stats



Test Results (Upper Limit = 4.7 (Ω))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	2.3459	2.3468	0.0009
2	0	Correlation	2.3439	2.3495	0.0056
4	50	Bias	2.3279	2.3608	0.0329
6	50	Bias	2.335	2.3615	0.0265
7	50	Bias	2.3448	2.3731	0.0283
8	50	Bias	2.3467	2.3802	0.0335
9	50	Bias	2.3412	2.369	0.0278
11	50	Unbias	2.3378	2.3517	0.0139
12	50	Unbias	2.3394	2.3608	0.0214
13	50	Unbias	2.3611	2.3651	0.004
14	50	Unbias	2.3454	2.3668	0.0214
15	50	Unbias	2.3562	2.3721	0.0159

TID vs Post - Pre Exposure Delta

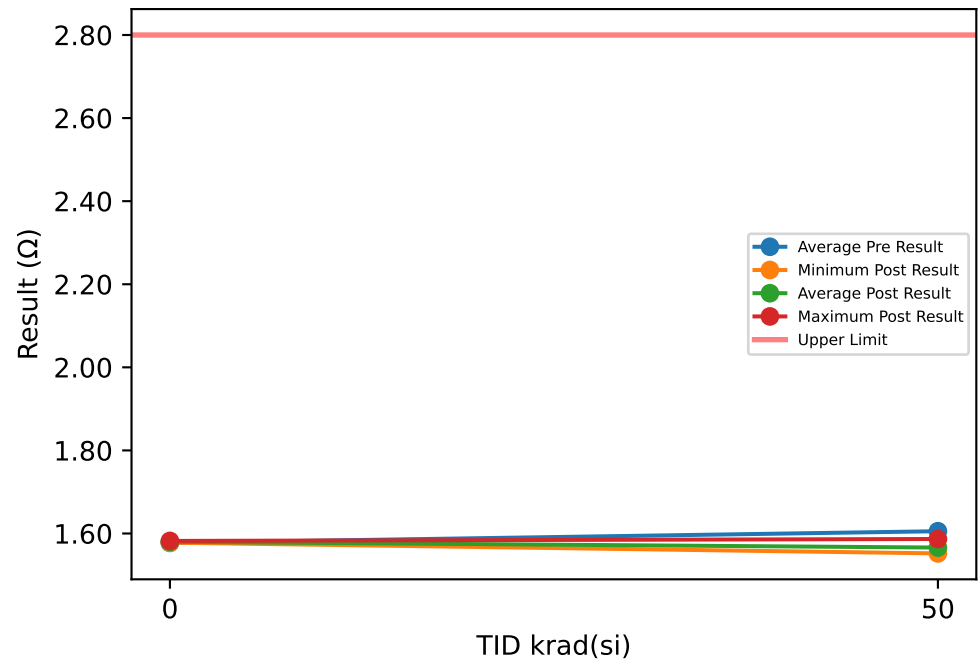


Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.3439	2.3449	2.3459	0.0014142	2.3468	2.3481	2.3495	0.0019092	0.0009	0.00325	0.0056	0.0033234
50	2.3279	2.3436	2.3611	0.0097568	2.3517	2.3661	2.3802	0.0080167	0.004	0.02256	0.0335	0.0092439

Device Test: 23.12 ROL(LEVEL|LS_RDSON/OUTL/14/14/100/0/5/500kHz//@ROL)

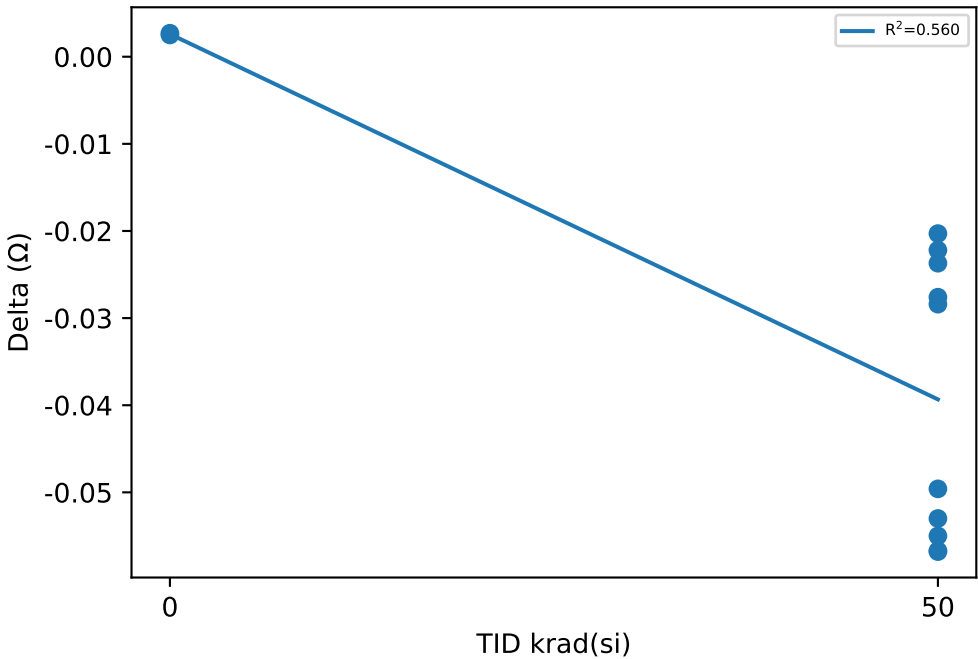
TID vs Result Stats



Test Results (Upper Limit = 2.8 (Ω))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.5752	1.5779	0.0027
2	0	Correlation	1.5796	1.5821	0.0025
4	50	Bias	1.623	1.568	-0.055
6	50	Bias	1.6017	1.5521	-0.0496
7	50	Bias	1.6107	1.5539	-0.0568
8	50	Bias	1.6159	1.5592	-0.0567
9	50	Bias	1.615	1.562	-0.053
11	50	Unbias	1.5912	1.5628	-0.0284
12	50	Unbias	1.5938	1.5662	-0.0276
13	50	Unbias	1.5849	1.5646	-0.0203
14	50	Unbias	1.6105	1.5868	-0.0237
15	50	Unbias	1.6081	1.5859	-0.0222

TID vs Post - Pre Exposure Delta

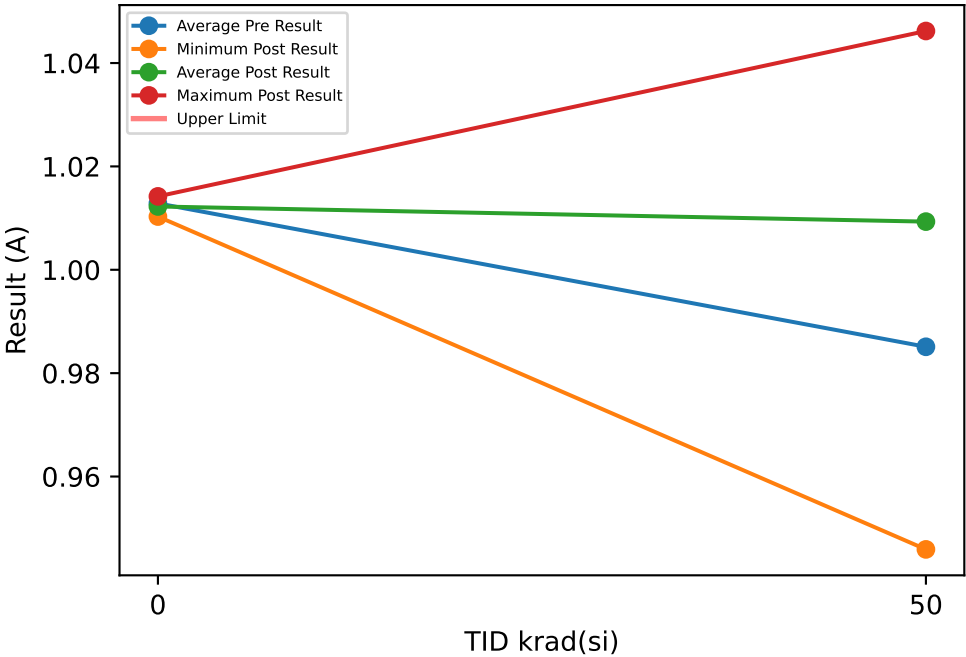


Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.5752	1.5774	1.5796	0.0031113	1.5779	1.58	1.5821	0.0029698	0.0025	0.0026	0.0027	0.00014142
50	1.5849	1.6055	1.623	0.012219	1.5521	1.5661	1.5868	0.011769	-0.0568	-0.03933	-0.0203	0.015992

Device Test: 23.2 OUT_IOL_4P5V(CURRENT|SINK/OUTL/4.5/4.5/0/0/4.5/500kHz//@OUT_IOL_4P5V)

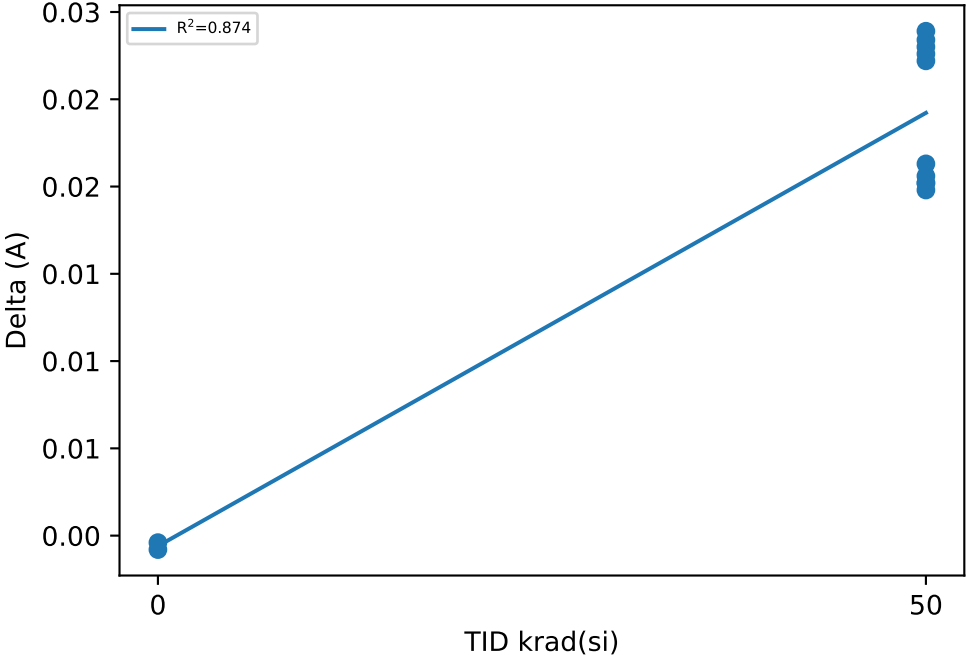
TID vs Result Stats



Test Results (No Limits Specified (A))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.0146	1.0142	-0.0004
2	0	Correlation	1.0111	1.0103	-0.0008
4	50	Bias	0.9257	0.9459	0.0202
6	50	Bias	1.013	1.0328	0.0198
7	50	Bias	1.0059	1.0265	0.0206
8	50	Bias	0.9751	0.9964	0.0213
9	50	Bias	0.9818	1.002	0.0202
11	50	Unbias	1.0012	1.0292	0.028
12	50	Unbias	0.9941	1.0213	0.0272
13	50	Unbias	1.0186	1.0462	0.0276
14	50	Unbias	1.0071	1.036	0.0289
15	50	Unbias	0.9285	0.9569	0.0284

TID vs Post - Pre Exposure Delta

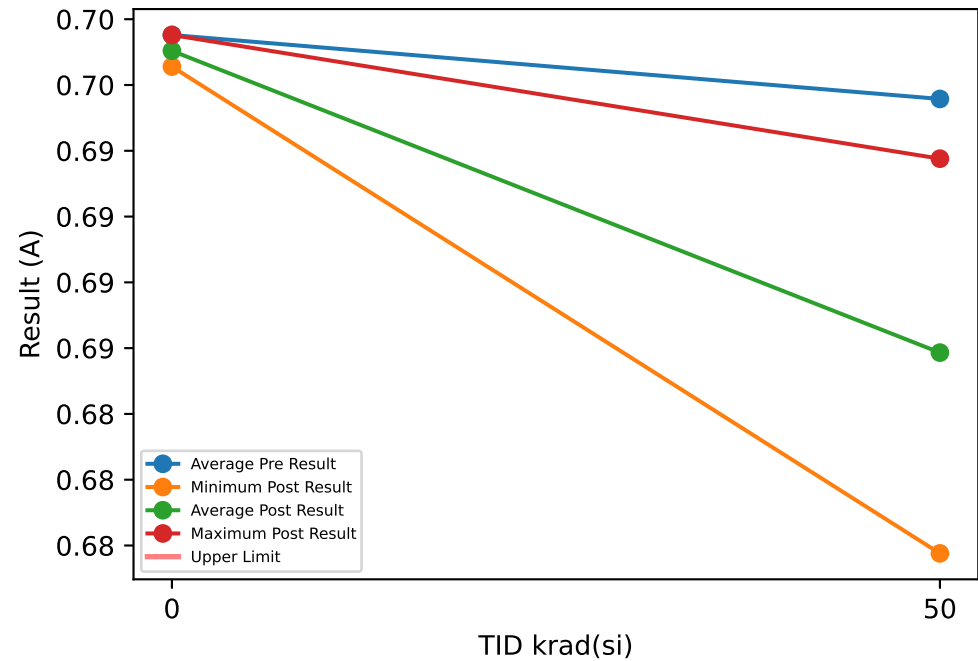


Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0111	1.0129	1.0146	0.0024749	1.0103	1.0122	1.0142	0.0027577	-0.0008	-0.0006	-0.0004	0.00028284
50	0.9257	0.9851	1.0186	0.033334	0.9459	1.0093	1.0462	0.034071	0.0198	0.02422	0.0289	0.0040477

Device Test: 23.3 OUT_IOH_5V(CURRENT|SOURCE/OUTH/5/5/0/0/5/500kHz//@OUT_IOH_5V)

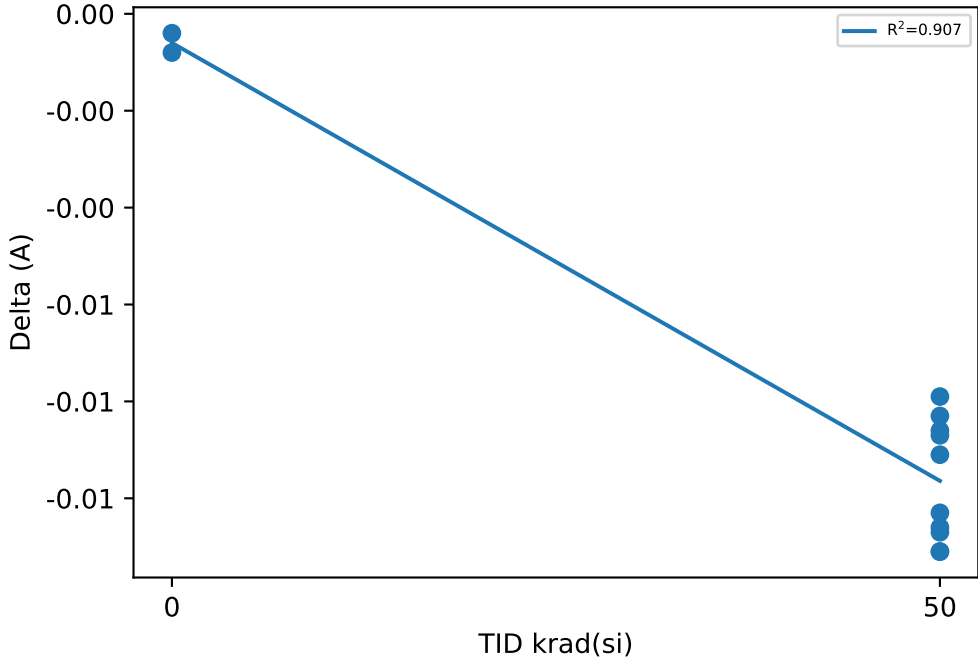
TID vs Result Stats



Test Results (No Limits Specified (A))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.6986	0.6982	-0.0004
2	0	Correlation	0.7002	0.6994	-0.0008
4	50	Bias	0.6927	0.684	-0.0087
6	50	Bias	0.6931	0.6852	-0.0079
7	50	Bias	0.6927	0.6844	-0.0083
8	50	Bias	0.6931	0.684	-0.0091
9	50	Bias	0.6883	0.6797	-0.0086
11	50	Unbias	0.7034	0.6931	-0.0103
12	50	Unbias	0.7053	0.6947	-0.0106
13	50	Unbias	0.7042	0.6931	-0.0111
14	50	Unbias	0.6947	0.6836	-0.0111
15	50	Unbias	0.7022	0.6915	-0.0107

TID vs Post - Pre Exposure Delta

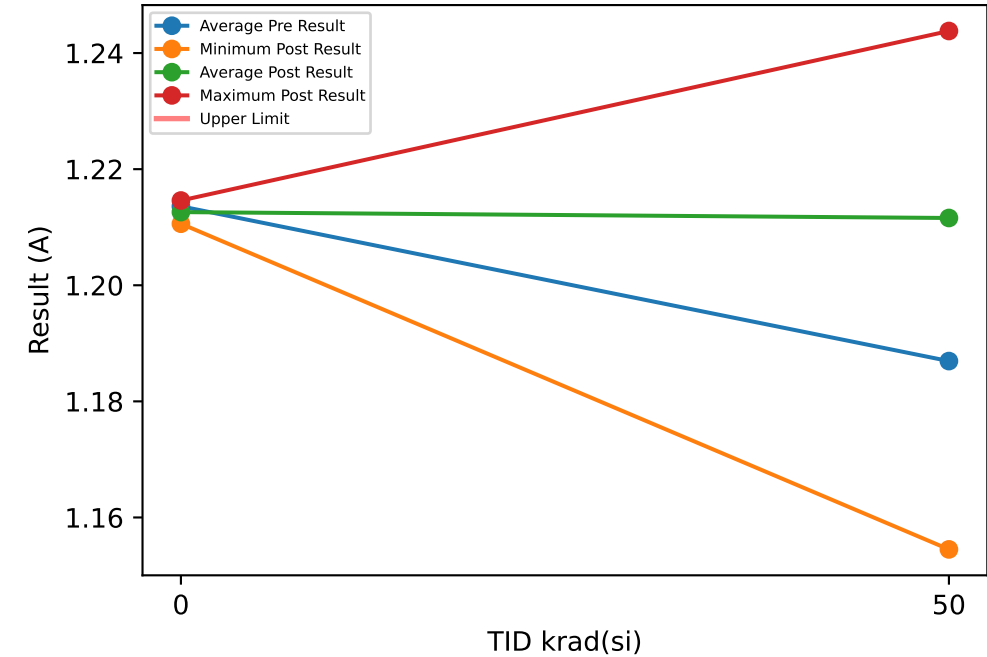


Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6986	0.6994	0.7002	0.0011314	0.6982	0.6988	0.6994	0.00084853	-0.0008	-0.0006	-0.0004	0.00028284
50	0.6883	0.69697	0.7053	0.0061201	0.6797	0.68733	0.6947	0.0052252	-0.0111	-0.00964	-0.0079	0.0012394

Device Test: 23.4 OUT_IOL_5V(CURRENT|SINK/OUTL/5/5/0/0/5/500kHz//@OUT_IOL_5V)

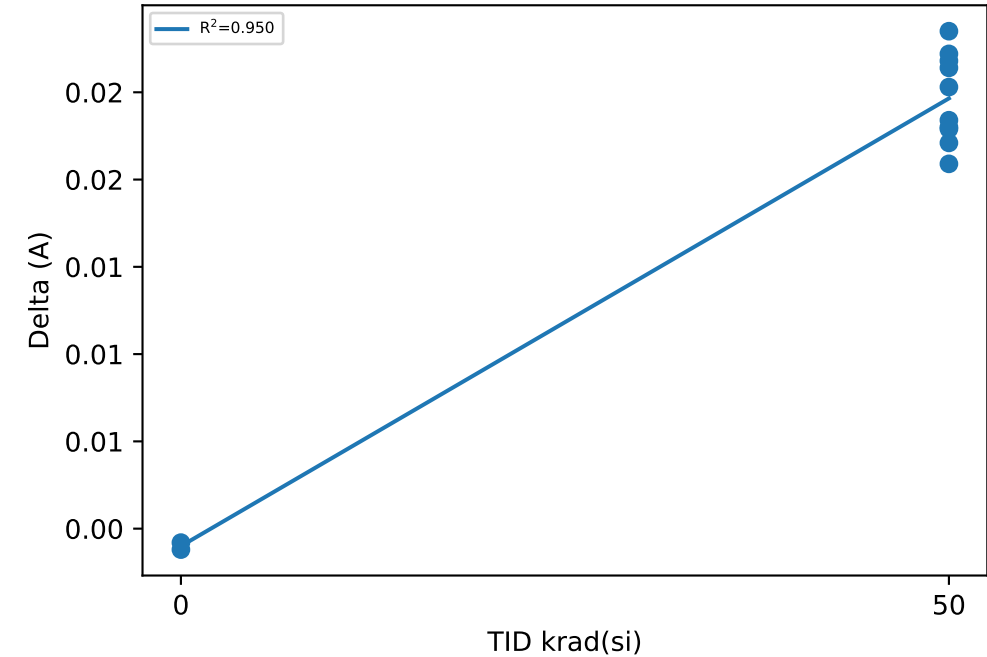
TID vs Result Stats



Test Results (No Limits Specified (A))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.2158	1.2146	-0.0012
2	0	Correlation	1.2114	1.2106	-0.0008
4	50	Bias	1.1336	1.1545	0.0209
6	50	Bias	1.2118	1.2348	0.023
7	50	Bias	1.2055	1.2284	0.0229
8	50	Bias	1.1778	1.2012	0.0234
9	50	Bias	1.1846	1.2067	0.0221
11	50	Unbias	1.2016	1.228	0.0264
12	50	Unbias	1.1964	1.2217	0.0253
13	50	Unbias	1.217	1.2438	0.0268
14	50	Unbias	1.2059	1.2344	0.0285
15	50	Unbias	1.1352	1.1624	0.0272

TID vs Post - Pre Exposure Delta

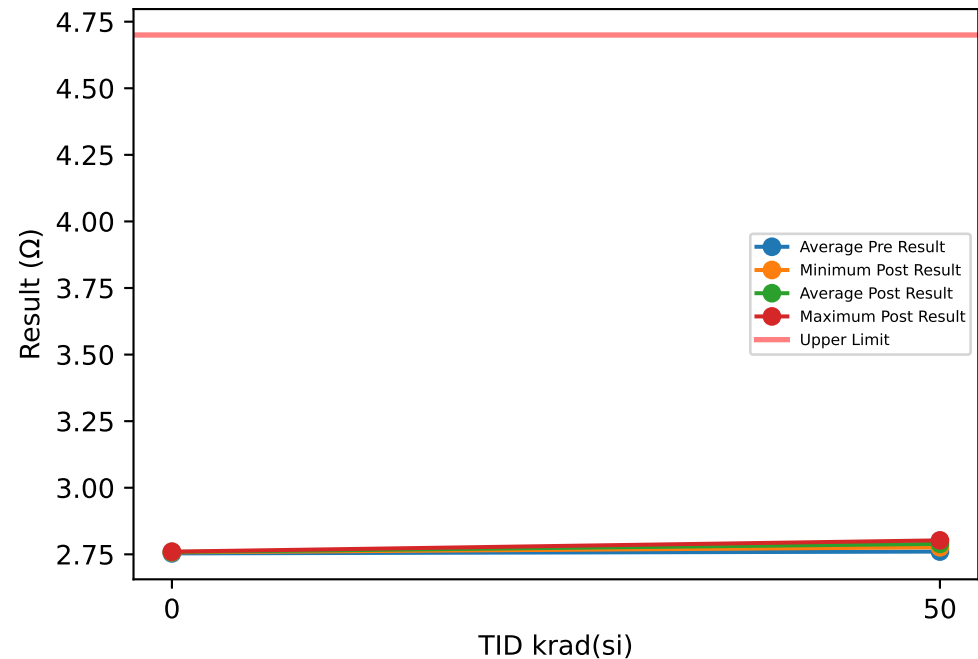


Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2114	1.2136	1.2158	0.0031113	1.2106	1.2126	1.2146	0.0028284	-0.0012	-0.001	-0.0008	0.00028284
50	1.1336	1.1869	1.217	0.030076	1.1545	1.2116	1.2438	0.030843	0.0209	0.02465	0.0285	0.0025242

Device Test: 23.5 ROH(LEVEL|HS_RDSON/OUTH/4.5/4.5/100/0/4.5/500kHz//@ROH)

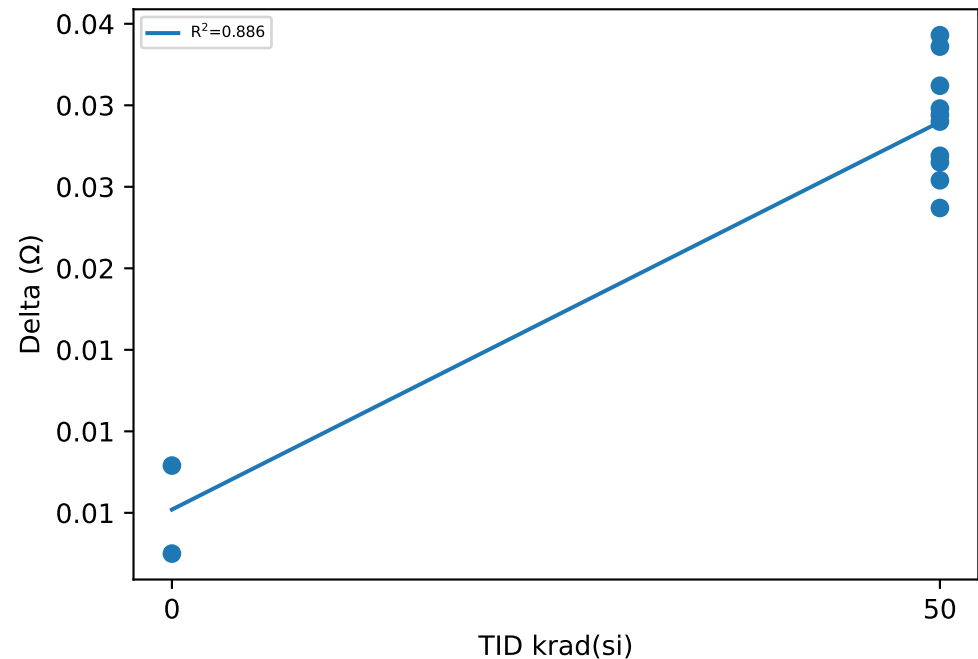
TID vs Result Stats



Test Results (Upper Limit = 4.7 (Ω))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	2.7522	2.7601	0.0079
2	0	Correlation	2.7548	2.7573	0.0025
4	50	Bias	2.7536	2.7848	0.0312
6	50	Bias	2.7719	2.8009	0.029
7	50	Bias	2.7582	2.7925	0.0343
8	50	Bias	2.7649	2.7947	0.0298
9	50	Bias	2.7689	2.8025	0.0336
11	50	Unbias	2.7546	2.7783	0.0237
12	50	Unbias	2.7494	2.7763	0.0269
13	50	Unbias	2.758	2.7834	0.0254
14	50	Unbias	2.7587	2.7881	0.0294
15	50	Unbias	2.7649	2.7914	0.0265

TID vs Post - Pre Exposure Delta

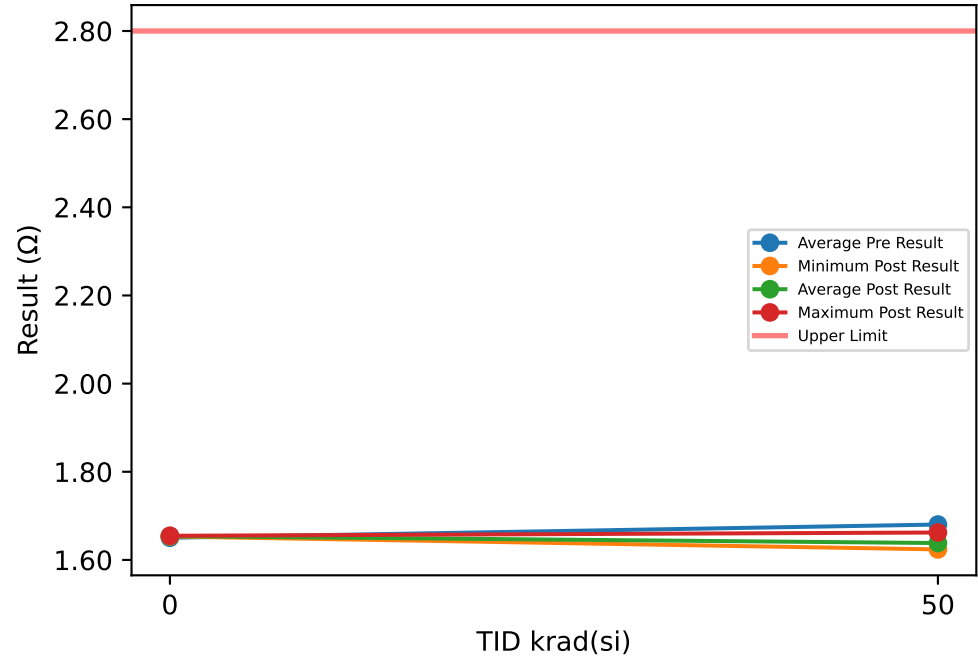


Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.7522	2.7535	2.7548	0.0018385	2.7573	2.7587	2.7601	0.0019799	0.0025	0.0052	0.0079	0.0038184
50	2.7494	2.7603	2.7719	0.0071437	2.7763	2.7893	2.8025	0.0088136	0.0237	0.02898	0.0343	0.0034415

Device Test: 23.6 ROL(LEVEL|LS_RDSON/OUTL/4.5/4.5/100/0/4.5/500kHz//@ROL)

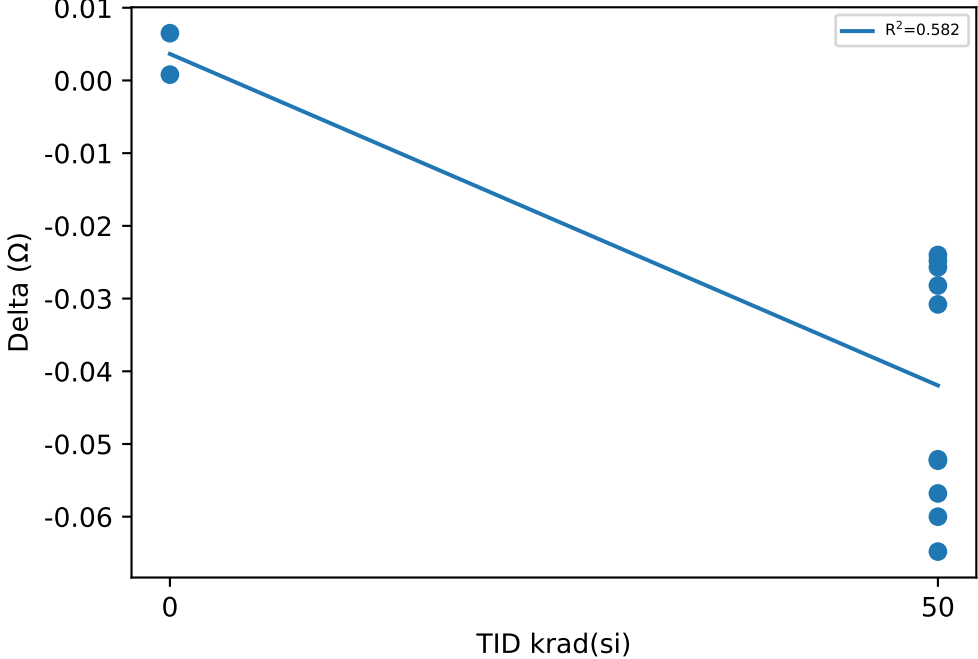
TID vs Result Stats



Test Results (Upper Limit = 2.8 (Ω))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.6467	1.6532	0.0065
2	0	Correlation	1.654	1.6548	0.0008
4	50	Bias	1.7073	1.6425	-0.0648
6	50	Bias	1.6762	1.6239	-0.0523
7	50	Bias	1.6798	1.6277	-0.0521
8	50	Bias	1.693	1.633	-0.06
9	50	Bias	1.6903	1.6335	-0.0568
11	50	Unbias	1.6647	1.6399	-0.0248
12	50	Unbias	1.6602	1.6345	-0.0257
13	50	Unbias	1.6602	1.6294	-0.0308
14	50	Unbias	1.6807	1.6567	-0.024
15	50	Unbias	1.6904	1.6622	-0.0282

TID vs Post - Pre Exposure Delta

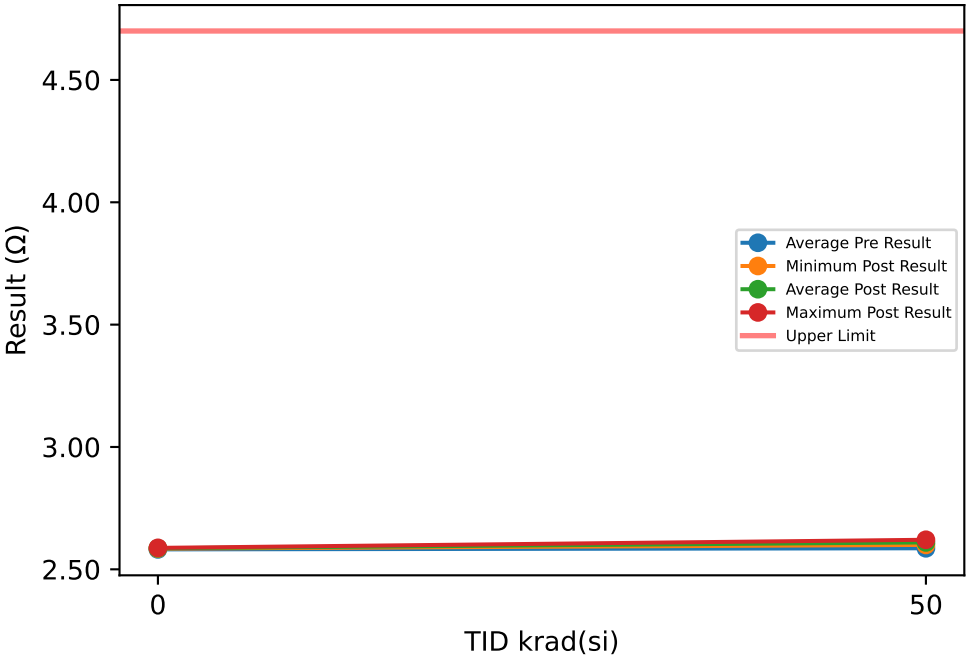


Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.6467	1.6503	1.654	0.0051619	1.6532	1.654	1.6548	0.0011314	0.0008	0.00365	0.0065	0.0040305
50	1.6602	1.6803	1.7073	0.015495	1.6239	1.6383	1.6622	0.012447	-0.0648	-0.04195	-0.024	0.016574

Device Test: 23.7 ROH(LEVEL|HS_RDSON/OUTH/5/5/100/0/5/500kHz//@ROH)

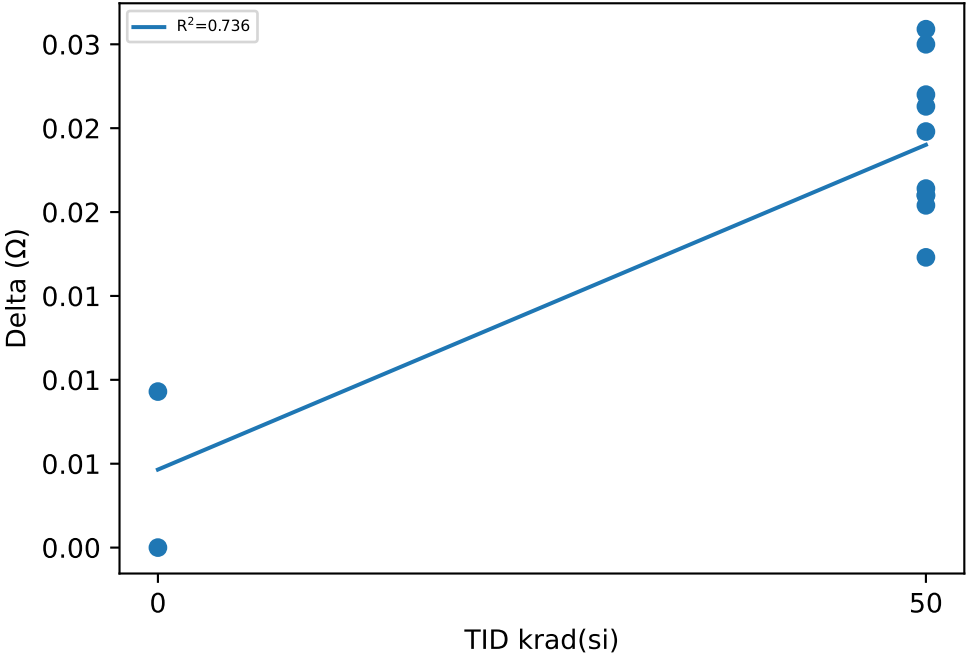
TID vs Result Stats



Test Results (Upper Limit = 4.7 (Ω))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	2.5784	2.5877	0.0093
2	0	Correlation	2.5845	2.5845	0
4	50	Bias	2.5796	2.6044	0.0248
6	50	Bias	2.5938	2.6208	0.027
7	50	Bias	2.5837	2.6137	0.03
8	50	Bias	2.5876	2.6139	0.0263
9	50	Bias	2.5886	2.6195	0.0309
11	50	Unbias	2.5829	2.6002	0.0173
12	50	Unbias	2.5793	2.5997	0.0204
13	50	Unbias	2.5859	2.6073	0.0214
14	50	Unbias	2.5843	2.6053	0.021
15	50	Unbias	2.5938	2.6148	0.021

TID vs Post - Pre Exposure Delta

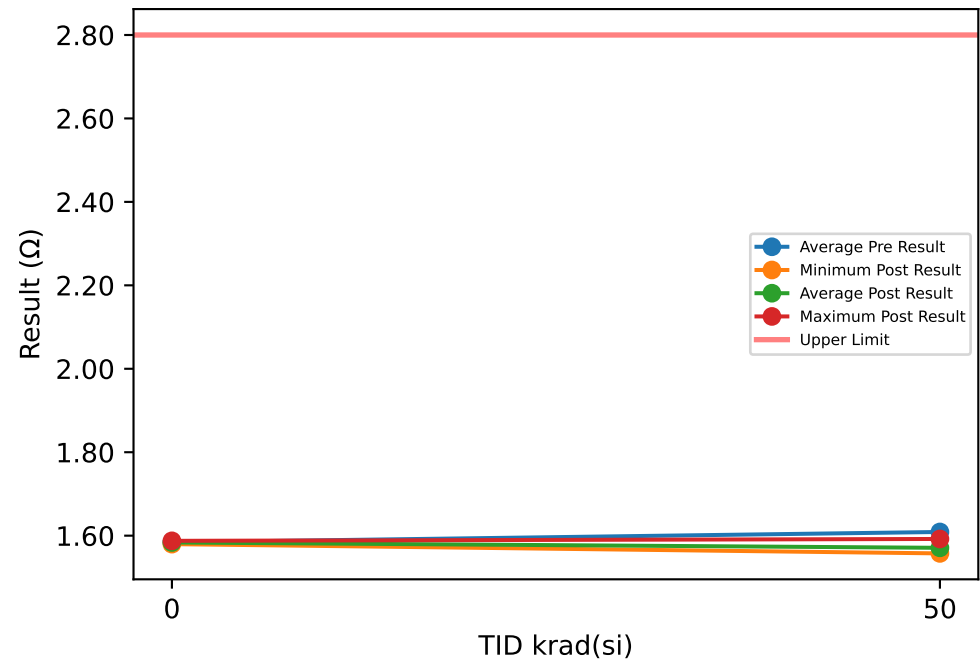


Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5784	2.5814	2.5845	0.0043134	2.5845	2.5861	2.5877	0.0022627	0	0.00465	0.0093	0.0065761
50	2.5793	2.5859	2.5938	0.0051058	2.5997	2.61	2.6208	0.0076135	0.0173	0.02401	0.0309	0.0044864

Device Test: 23.8 ROL(LEVEL|LS_RDSON/OUTL/5/5/100/0/5/500kHz//@ROL)

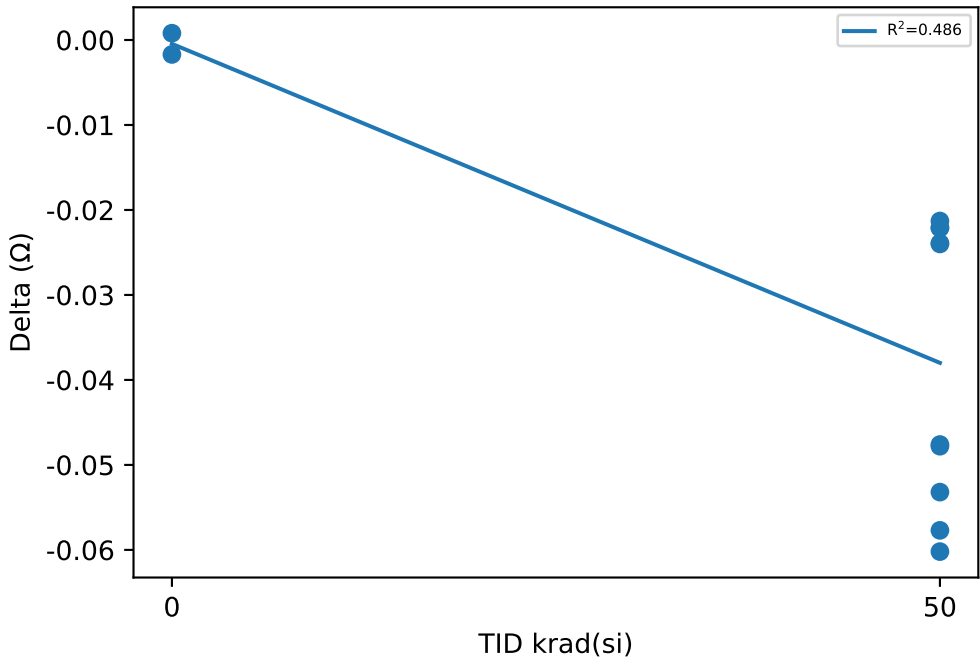
TID vs Result Stats



Test Results (Upper Limit = 2.8 (Ω))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.5814	1.5797	-0.0017
2	0	Correlation	1.5868	1.5876	0.0008
4	50	Bias	1.6284	1.5707	-0.0577
6	50	Bias	1.6051	1.5575	-0.0476
7	50	Bias	1.6125	1.5593	-0.0532
8	50	Bias	1.6212	1.561	-0.0602
9	50	Bias	1.6168	1.569	-0.0478
11	50	Unbias	1.5929	1.569	-0.0239
12	50	Unbias	1.5948	1.5735	-0.0213
13	50	Unbias	1.5902	1.5681	-0.0221
14	50	Unbias	1.6125	1.5885	-0.024
15	50	Unbias	1.6142	1.5921	-0.0221

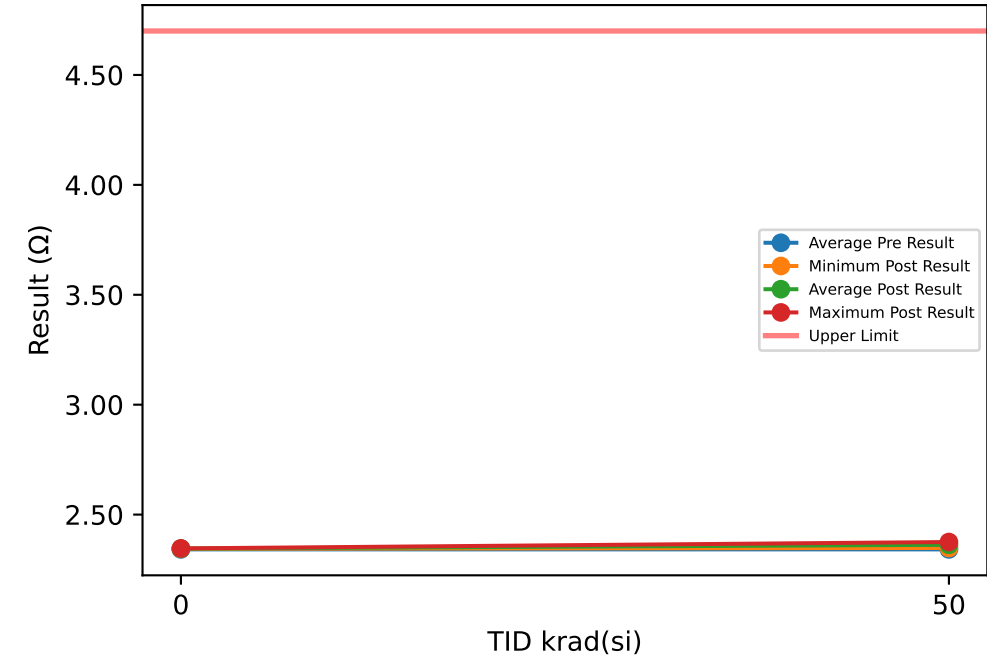
TID vs Post - Pre Exposure Delta



Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.5814	1.5841	1.5868	0.0038184	1.5797	1.5837	1.5876	0.0055861	-0.0017	-0.00045	0.0008	0.0017678
50	1.5902	1.6089	1.6284	0.012767	1.5575	1.5709	1.5921	0.011514	-0.0602	-0.03799	-0.0213	0.016598

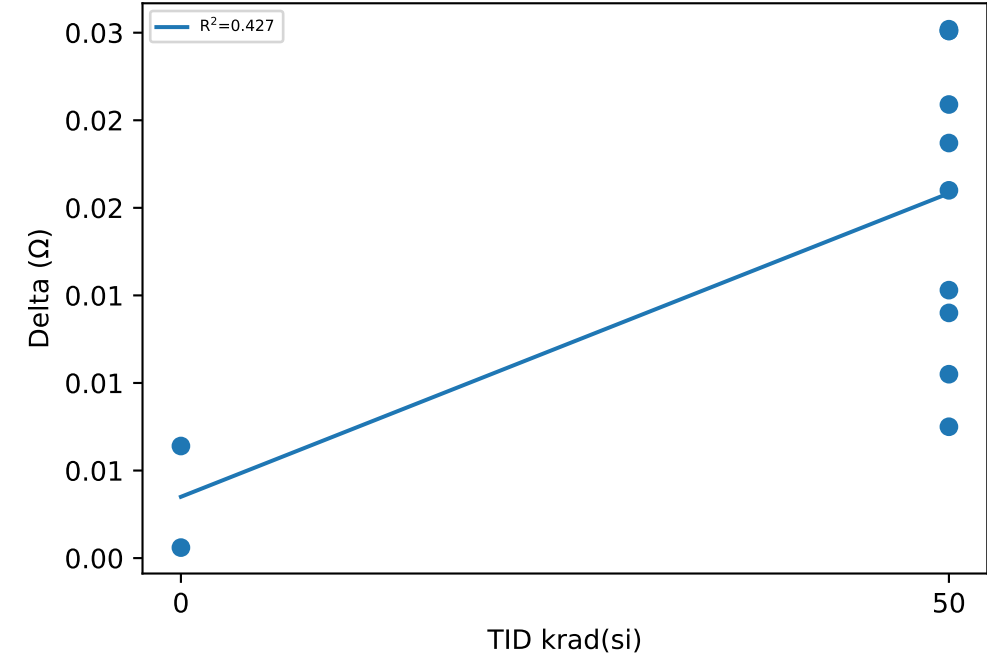
TID vs Result Stats



Test Results (Upper Limit = 4.7 (Ω))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	2.3398	2.3462	0.0064
2	0	Correlation	2.3438	2.3444	0.0006
4	50	Bias	2.3294	2.3531	0.0237
6	50	Bias	2.3284	2.3585	0.0301
7	50	Bias	2.3417	2.3718	0.0301
8	50	Bias	2.345	2.3752	0.0302
9	50	Bias	2.3363	2.3622	0.0259
11	50	Unbias	2.3327	2.348	0.0153
12	50	Unbias	2.3394	2.3604	0.021
13	50	Unbias	2.3561	2.3701	0.014
14	50	Unbias	2.3497	2.3602	0.0105
15	50	Unbias	2.358	2.3655	0.0075

TID vs Post - Pre Exposure Delta

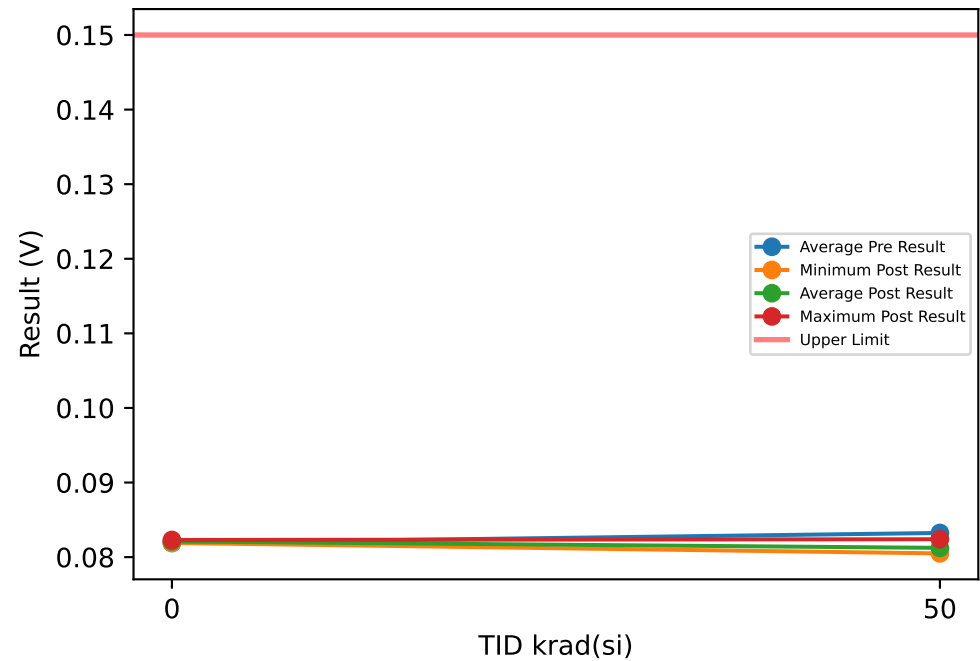


Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.3398	2.3418	2.3438	0.0028284	2.3444	2.3453	2.3462	0.0012728	0.0006	0.0035	0.0064	0.0041012
50	2.3284	2.3417	2.358	0.010496	2.348	2.3625	2.3752	0.0084258	0.0075	0.02083	0.0302	0.0085327

Device Test: 24.1 OUT_VOL(LEVEL|LOW_LEVEL/OUTL/4.5/4.5/0/0/4.5/500kHz//@OUT_VOL)

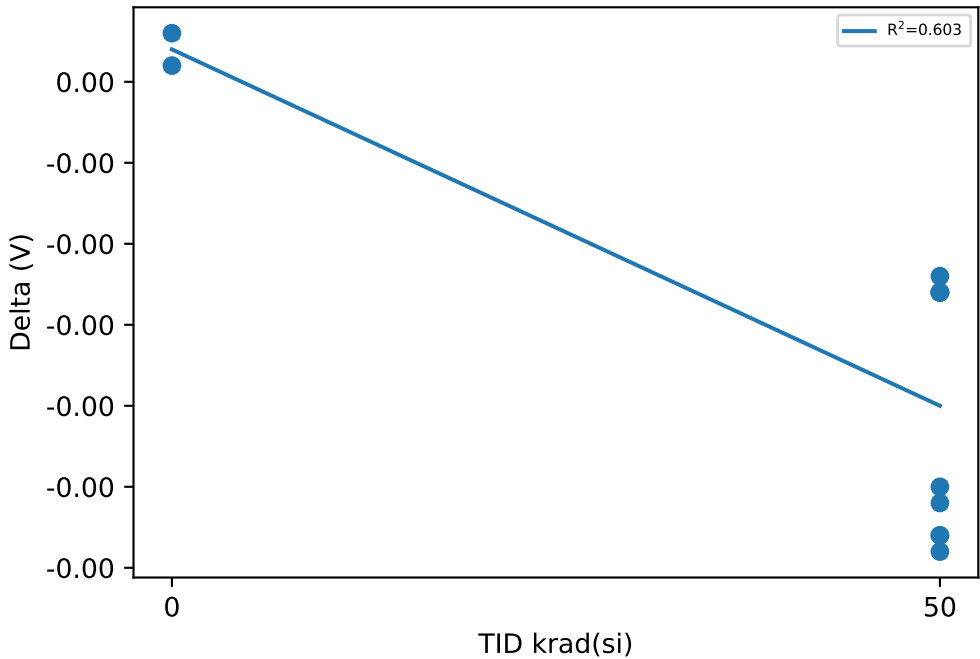
TID vs Result Stats



Test Results (Upper Limit = 0.15 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.0818	0.0819	0.0001
2	0	Correlation	0.082	0.0823	0.0003
4	50	Bias	0.0844	0.0816	-0.0028
6	50	Bias	0.0831	0.0805	-0.0026
7	50	Bias	0.0833	0.0805	-0.0028
8	50	Bias	0.0838	0.0809	-0.0029
9	50	Bias	0.0836	0.0811	-0.0025
11	50	Unbias	0.0825	0.0812	-0.0013
12	50	Unbias	0.0824	0.0811	-0.0013
13	50	Unbias	0.0823	0.081	-0.0013
14	50	Unbias	0.0834	0.0821	-0.0013
15	50	Unbias	0.0836	0.0824	-0.0012

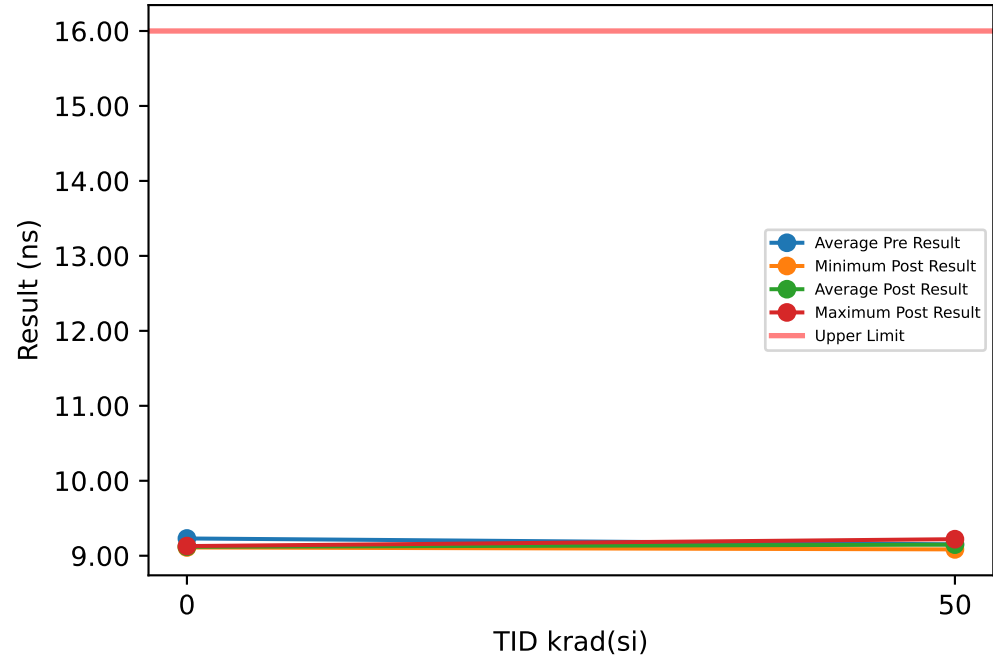
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0818	0.0819	0.082	0.00014142	0.0819	0.0821	0.0823	0.00028284	0.0001	0.0002	0.0003	0.00014142
50	0.0823	0.08324	0.0844	0.00067528	0.0805	0.08124	0.0824	0.00062574	-0.0029	-0.002	-0.0012	0.00076739

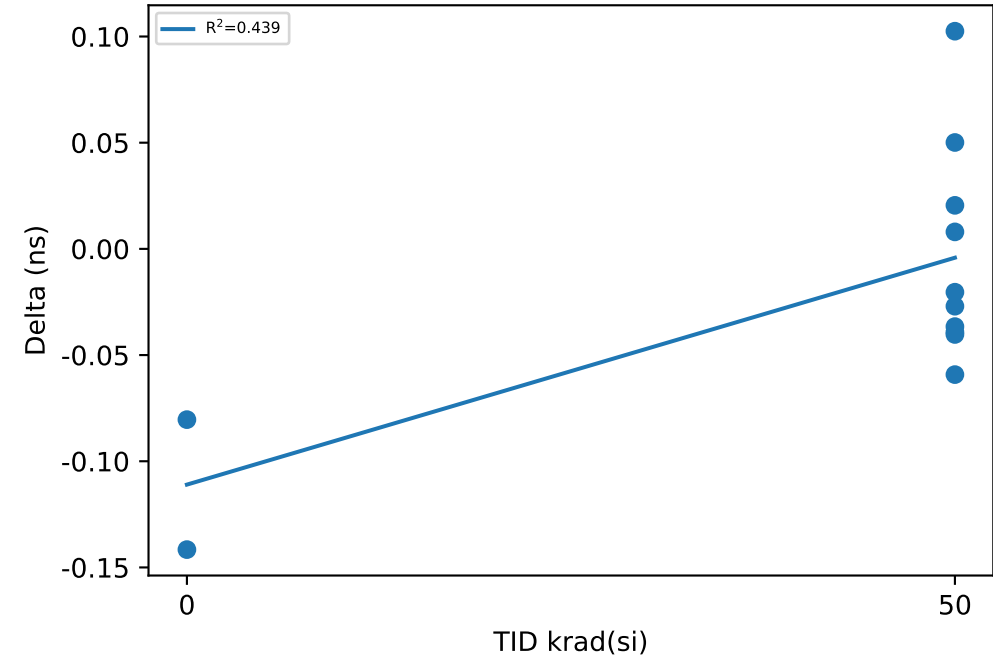
TID vs Result Stats



Test Results (Upper Limit = 16.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	9.2516	9.11	-0.1416
2	0	Correlation	9.2093	9.1288	-0.0804
4	50	Bias	9.1707	9.2208	0.0501
6	50	Bias	9.1423	9.1628	0.0205
7	50	Bias	9.1366	9.1447	0.008
8	50	Bias	9.2174	9.1771	-0.0403
9	50	Bias	9.1633	9.1267	-0.0366
11	50	Unbias	9.1806	9.1537	-0.027
12	50	Unbias	9.0991	9.2017	0.1025
13	50	Unbias	9.1237	9.0846	-0.0392
14	50	Unbias	9.1393	9.1189	-0.0204
15	50	Unbias	9.148	9.0889	-0.0592

TID vs Post - Pre Exposure Delta

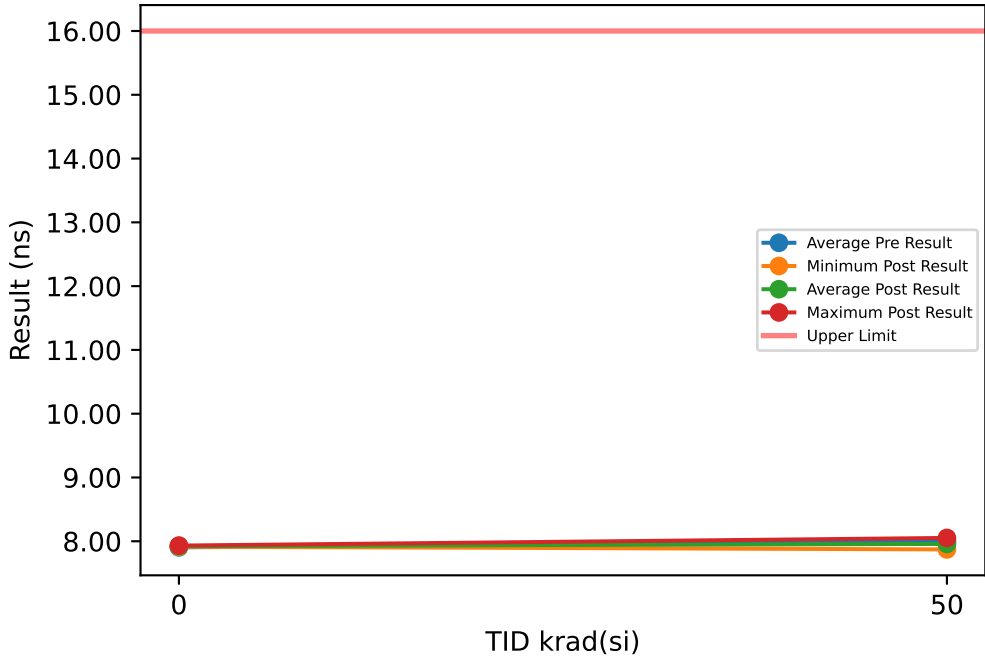


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.2093	9.2305	9.2516	0.029981	9.11	9.1195	9.1288	0.013294	-0.1416	-0.111	-0.0804	0.043275
50	9.0991	9.1521	9.2174	0.032797	9.0846	9.148	9.2208	0.044854	-0.0592	-0.00416	0.1025	0.049975

Device Test: 24.18 OUT_FALL_LDO(TIMING|OUT_FALL/OUTH/4.5/12/0/1000/4.5/500kHz//@OUT_FALL_LDO)

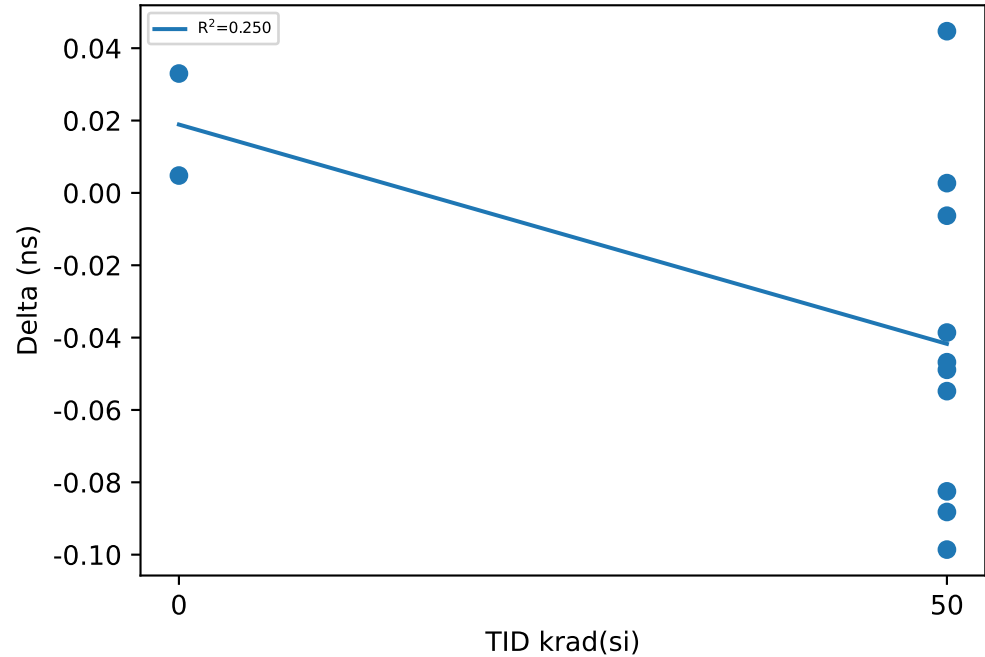
TID vs Result Stats



Test Results (Upper Limit = 16.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.8993	7.9323	0.033
2	0	Correlation	7.91	7.9148	0.0048
4	50	Bias	8.0903	7.9917	-0.0986
6	50	Bias	7.9607	7.8725	-0.0882
7	50	Bias	7.979	7.9727	-0.0063
8	50	Bias	7.9759	7.9786	0.0027
9	50	Bias	7.9982	7.9157	-0.0825
11	50	Unbias	8.0088	7.954	-0.0548
12	50	Unbias	7.9726	7.934	-0.0386
13	50	Unbias	7.949	7.9001	-0.0489
14	50	Unbias	7.9668	8.0115	0.0447
15	50	Unbias	8.0988	8.052	-0.0468

TID vs Post - Pre Exposure Delta

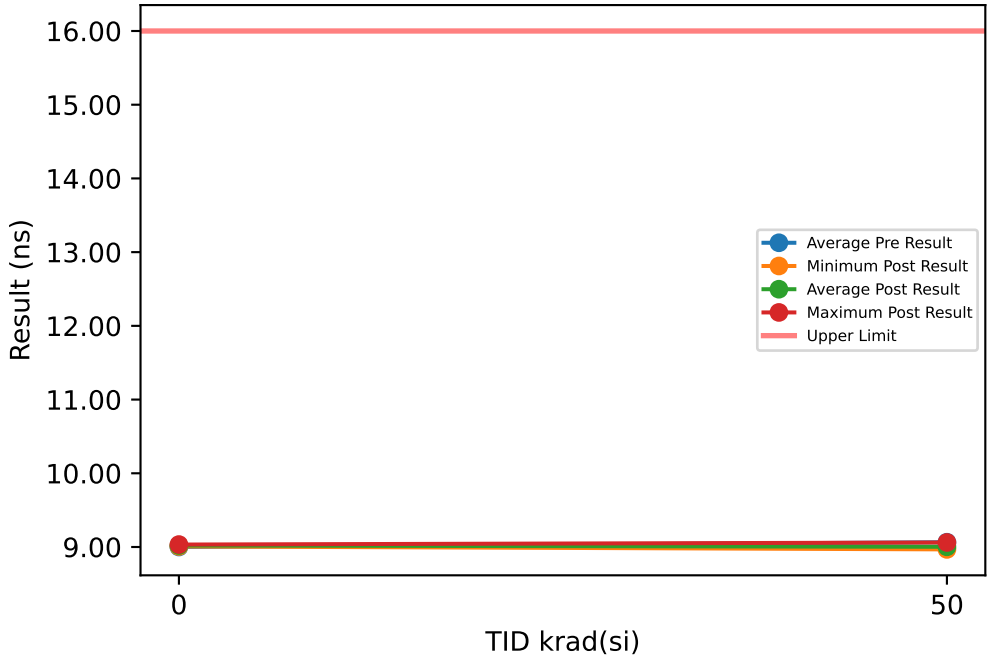


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.8993	7.9047	7.91	0.007566	7.9148	7.9235	7.9323	0.012374	0.0048	0.0189	0.033	0.01994
50	7.949	8	8.0988	0.052722	7.8725	7.9583	8.052	0.054281	-0.0986	-0.04173	0.0447	0.044738

Device Test: 24.19 OUT_RISE_LDO(TIMING|OUT_RISE/OUTH/5/12/0/1000/5/500kHz//@OUT_RISE_LDO)

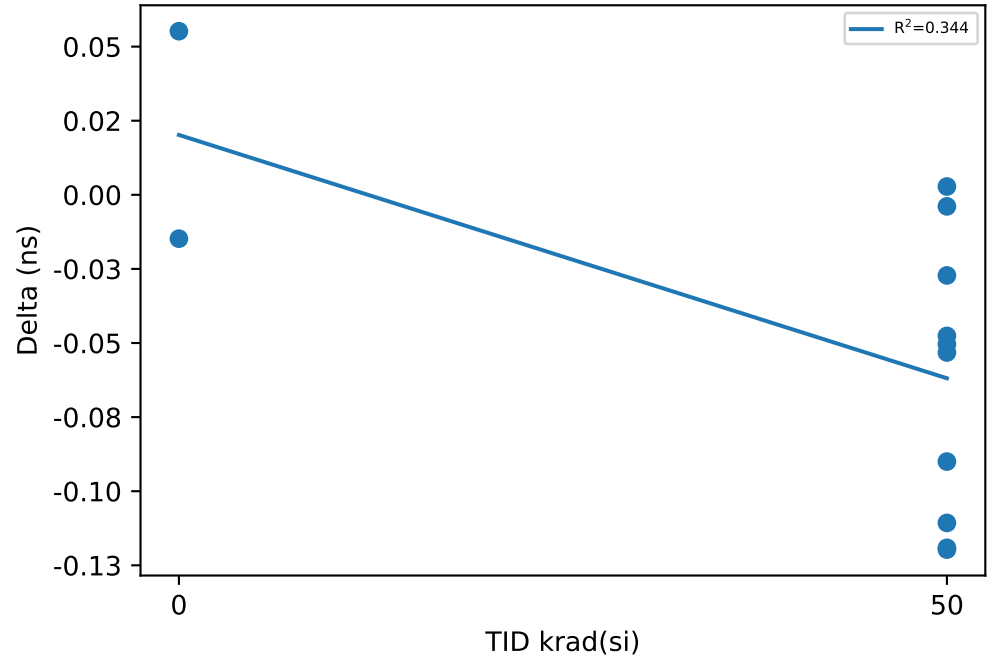
TID vs Result Stats



Test Results (Upper Limit = 16.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	9.0223	9.0076	-0.0148
2	0	Correlation	8.9779	9.0331	0.0552
4	50	Bias	9.1027	8.983	-0.1197
6	50	Bias	9.0184	8.968	-0.0504
7	50	Bias	9.0457	9.0419	-0.0039
8	50	Bias	9.1129	8.9939	-0.1191
9	50	Bias	9.0782	8.9674	-0.1107
11	50	Unbias	9.0607	9.013	-0.0476
12	50	Unbias	9.0777	8.9877	-0.09
13	50	Unbias	9.0231	8.996	-0.0272
14	50	Unbias	9.0695	9.0163	-0.0532
15	50	Unbias	9.0585	9.0612	0.0028

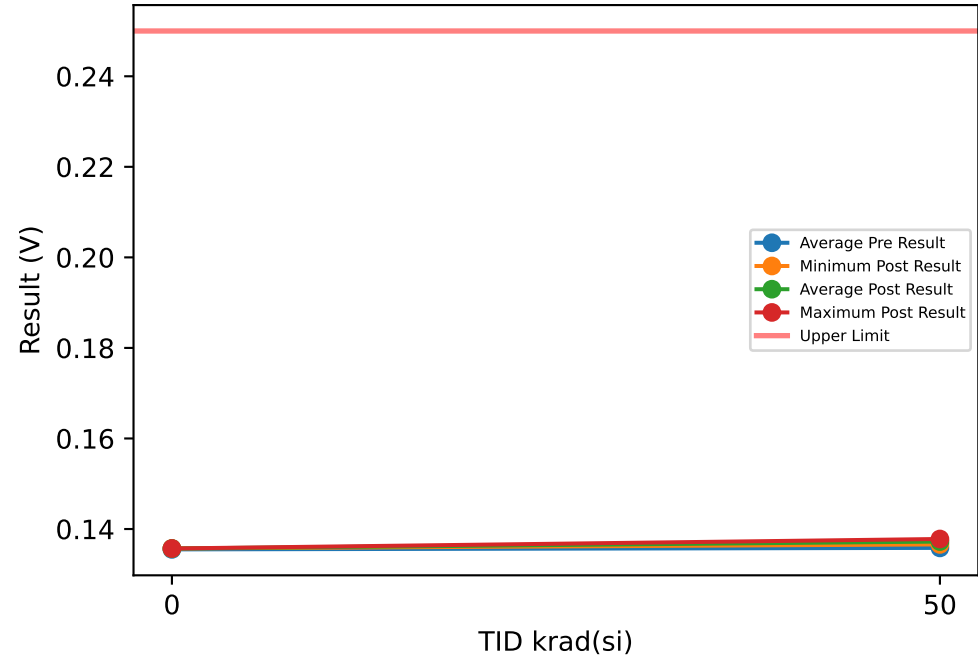
TID vs Post - Pre Exposure Delta



Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.9779	9.0001	9.0223	0.031396	9.0076	9.0204	9.0331	0.018102	-0.0148	0.0202	0.0552	0.049497
50	9.0184	9.0647	9.1129	0.030588	8.9674	9.0028	9.0612	0.030619	-0.1197	-0.0619	0.0028	0.045887

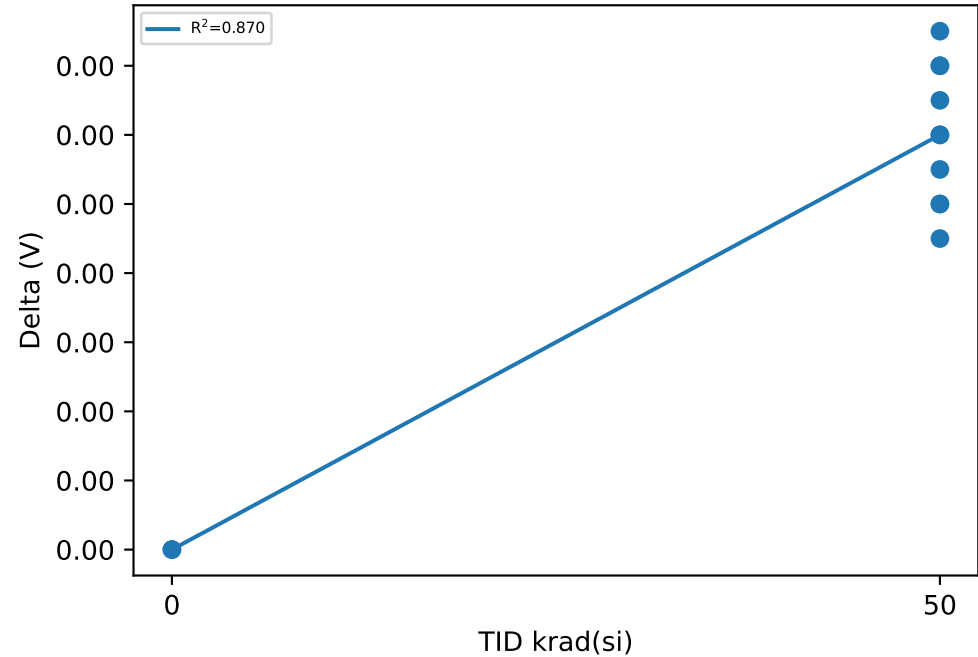
TID vs Result Stats



Test Results (Upper Limit = 0.25 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.1355	0.1357	0.0002
2	0	Correlation	0.1355	0.1357	0.0002
4	50	Bias	0.1354	0.137	0.0016
6	50	Bias	0.1364	0.1378	0.0014
7	50	Bias	0.1357	0.1374	0.0017
8	50	Bias	0.1359	0.1375	0.0016
9	50	Bias	0.1363	0.1378	0.0015
11	50	Unbias	0.1356	0.1368	0.0012
12	50	Unbias	0.1354	0.1366	0.0012
13	50	Unbias	0.1357	0.137	0.0013
14	50	Unbias	0.1357	0.1371	0.0014
15	50	Unbias	0.1362	0.1373	0.0011

TID vs Post - Pre Exposure Delta

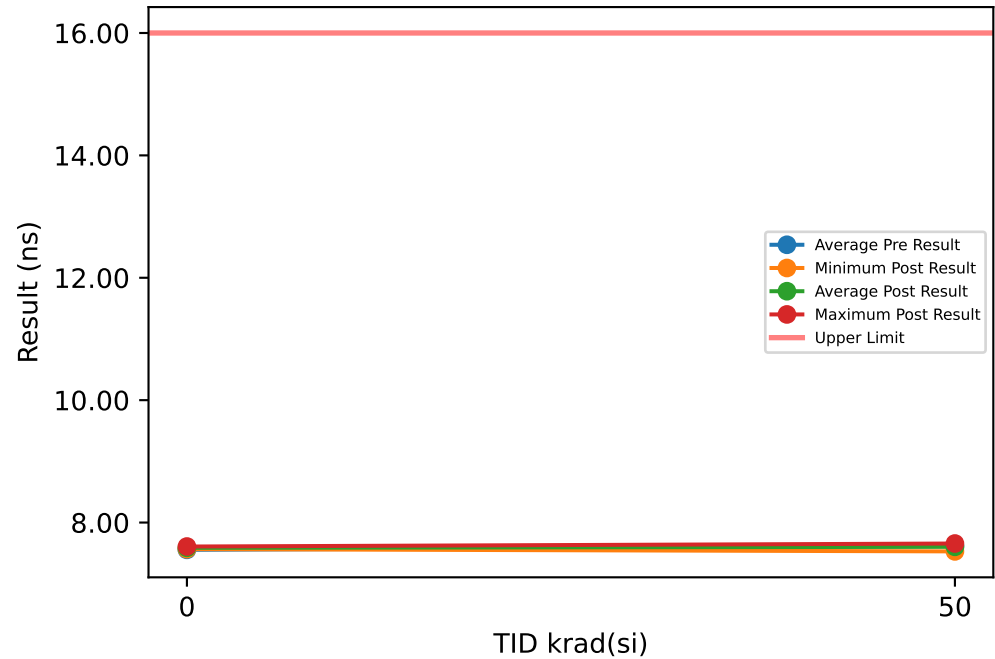


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1355	0.1355	0.1355	0	0.1357	0.1357	0.1357	0	0.0002	0.0002	0.0002	0
50	0.1354	0.13583	0.1364	0.00035917	0.1366	0.13723	0.1378	0.00040291	0.0011	0.0014	0.0017	0.0002

Device Test: 24.20 OUT_FALL_LDO(TIMING|OUT_FALL/OUTH/5/12/0/1000/5/500kHz//@OUT_FALL_LDO)

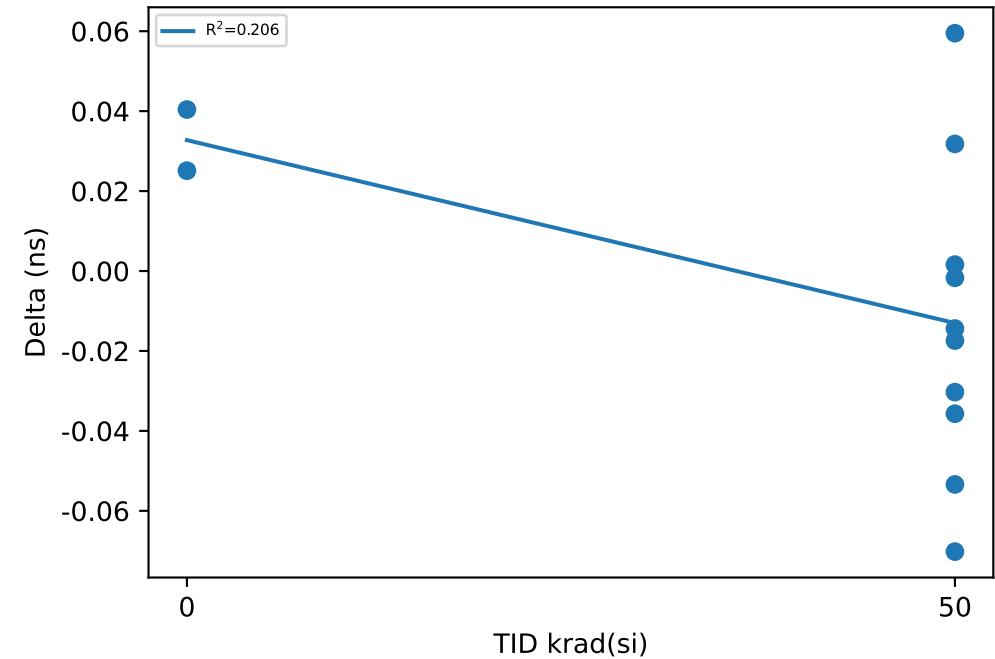
TID vs Result Stats



Test Results (Upper Limit = 16.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.583	7.6081	0.0251
2	0	Correlation	7.5252	7.5656	0.0404
4	50	Bias	7.7274	7.6572	-0.0702
6	50	Bias	7.5518	7.5836	0.0318
7	50	Bias	7.5543	7.6138	0.0595
8	50	Bias	7.5892	7.5535	-0.0357
9	50	Bias	7.6339	7.6036	-0.0303
11	50	Unbias	7.637	7.6386	0.0016
12	50	Unbias	7.6731	7.6197	-0.0534
13	50	Unbias	7.5429	7.5285	-0.0144
14	50	Unbias	7.6348	7.6174	-0.0174
15	50	Unbias	7.6188	7.6171	-0.0017

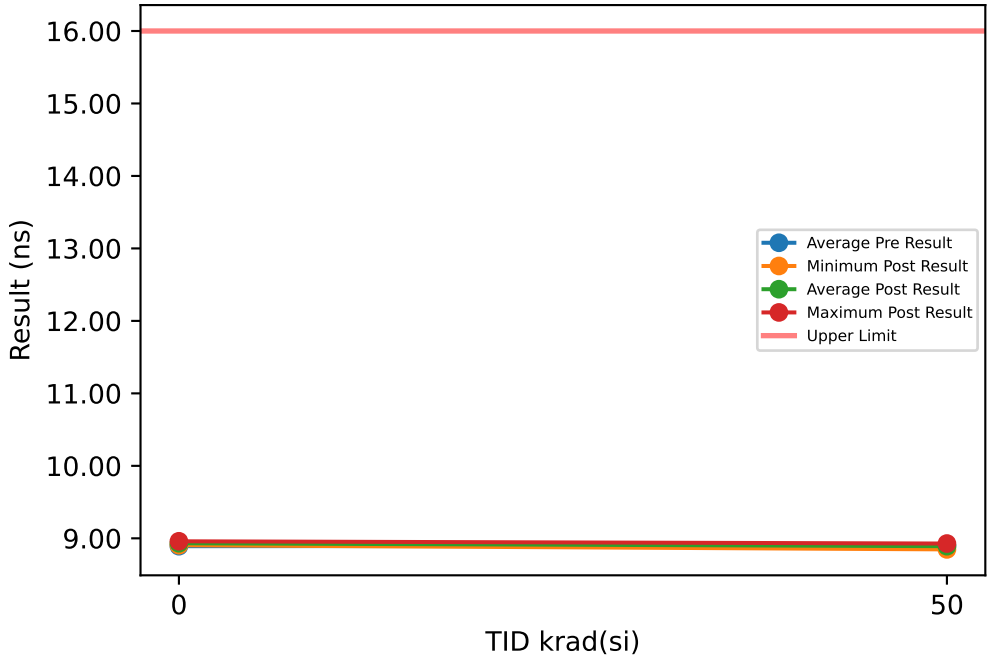
TID vs Post - Pre Exposure Delta



Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.5252	7.5541	7.583	0.040871	7.5656	7.5869	7.6081	0.030052	0.0251	0.03275	0.0404	0.010819
50	7.5429	7.6163	7.7274	0.058483	7.5285	7.6033	7.6572	0.038562	-0.0702	-0.01302	0.0595	0.038505

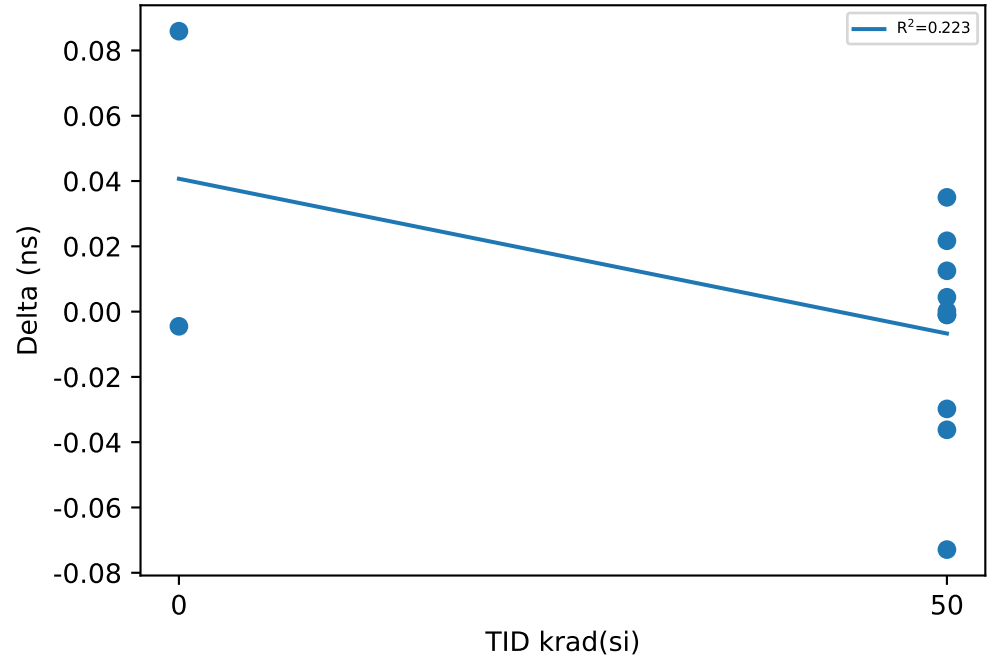
TID vs Result Stats



Test Results (Upper Limit = 16.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	8.8733	8.9591	0.0859
2	0	Correlation	8.9094	8.9049	-0.0045
4	50	Bias	8.8788	8.849	-0.0298
6	50	Bias	8.8806	8.8809	0.0002
7	50	Bias	8.8994	8.9038	0.0044
8	50	Bias	8.9697	8.8969	-0.0729
9	50	Bias	8.9038	8.9027	-0.001
11	50	Unbias	8.9142	8.9132	-0.001
12	50	Unbias	8.8799	8.9017	0.0217
13	50	Unbias	8.8834	8.8473	-0.0362
14	50	Unbias	8.8931	8.9281	0.035
15	50	Unbias	8.8798	8.8924	0.0125

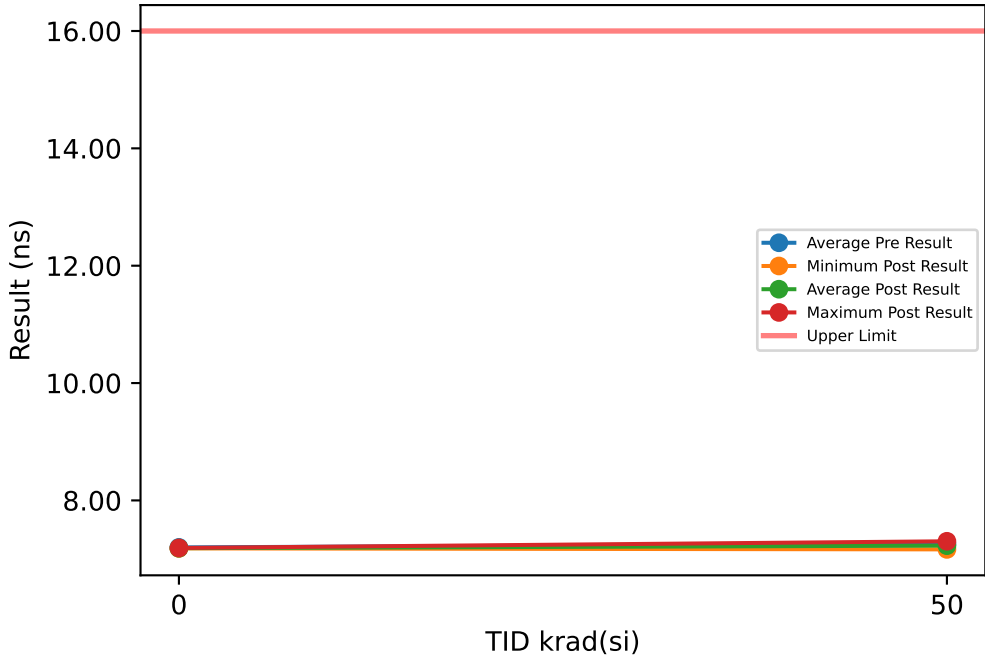
TID vs Post - Pre Exposure Delta



Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.8733	8.8913	8.9094	0.025597	8.9049	8.9321	8.9591	0.038325	-0.0045	0.0407	0.0859	0.063922
50	8.8788	8.8983	8.9697	0.027907	8.8473	8.8916	8.9281	0.026034	-0.0729	-0.00671	0.035	0.03151

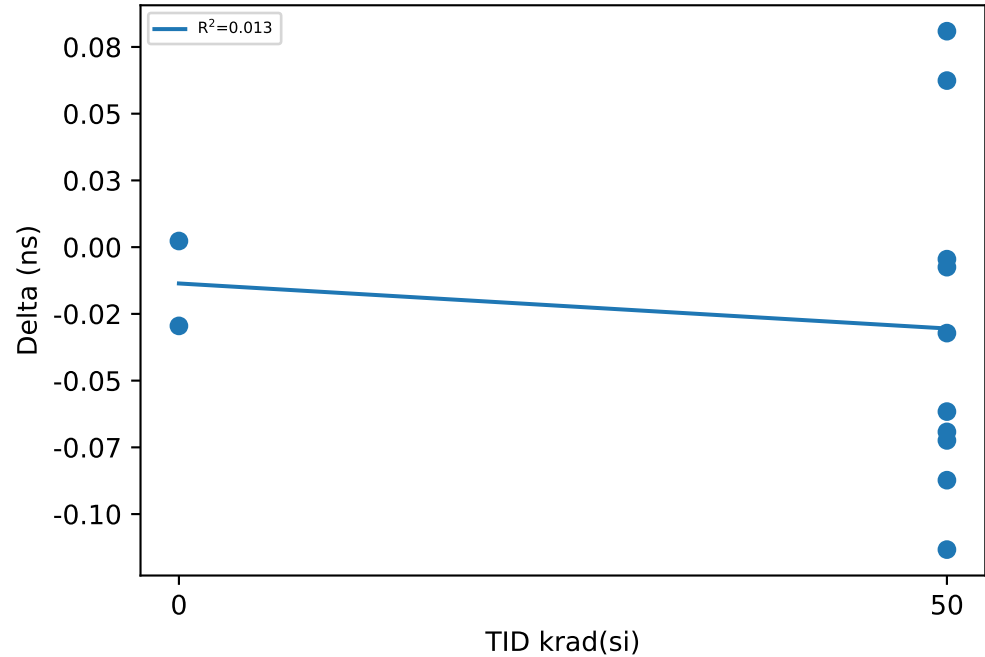
TID vs Result Stats



Test Results (Upper Limit = 16.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.2119	7.1824	-0.0295
2	0	Correlation	7.1875	7.1898	0.0023
4	50	Bias	7.3934	7.2801	-0.1133
6	50	Bias	7.2438	7.1714	-0.0724
7	50	Bias	7.2354	7.2309	-0.0045
8	50	Bias	7.2354	7.2032	-0.0322
9	50	Bias	7.2227	7.3036	0.0809
11	50	Unbias	7.2288	7.2213	-0.0075
12	50	Unbias	7.2673	7.2057	-0.0616
13	50	Unbias	7.2345	7.1653	-0.0692
14	50	Unbias	7.1983	7.2607	0.0624
15	50	Unbias	7.337	7.2497	-0.0873

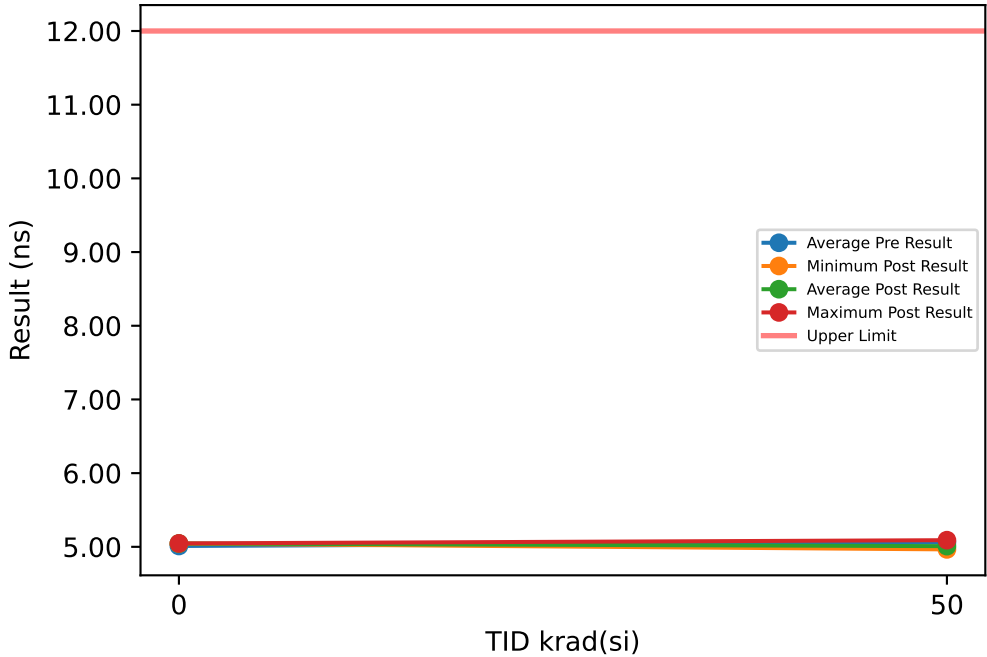
TID vs Post - Pre Exposure Delta



Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.1875	7.1997	7.2119	0.017253	7.1824	7.1861	7.1898	0.0052326	-0.0295	-0.0136	0.0023	0.022486
50	7.1983	7.2597	7.3934	0.059695	7.1653	7.2292	7.3036	0.045039	-0.1133	-0.03047	0.0809	0.063728

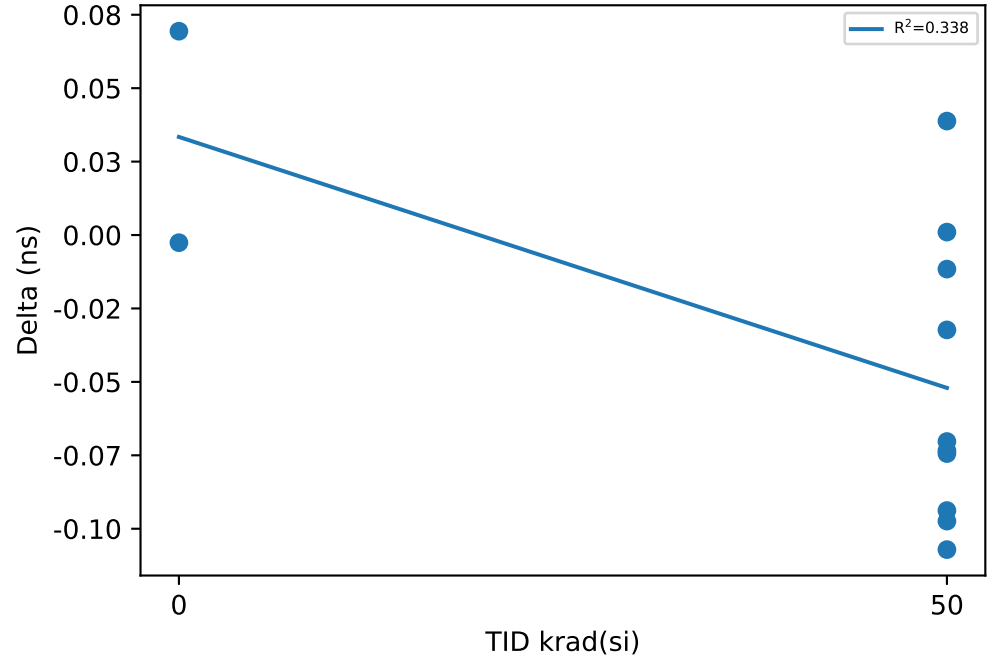
TID vs Result Stats



Test Results (Upper Limit = 12.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0457	5.0431	-0.0026
2	0	Correlation	4.977	5.0464	0.0694
4	50	Bias	5.1044	5.007	-0.0974
6	50	Bias	5.0071	4.9955	-0.0116
7	50	Bias	5.0722	4.9651	-0.1071
8	50	Bias	5.0661	4.9927	-0.0734
9	50	Bias	5.023	5.0618	0.0388
11	50	Unbias	5.0469	4.9725	-0.0744
12	50	Unbias	5.0517	4.9814	-0.0703
13	50	Unbias	5.0655	4.9717	-0.0938
14	50	Unbias	5.0892	5.0902	0.001
15	50	Unbias	5.0855	5.0532	-0.0323

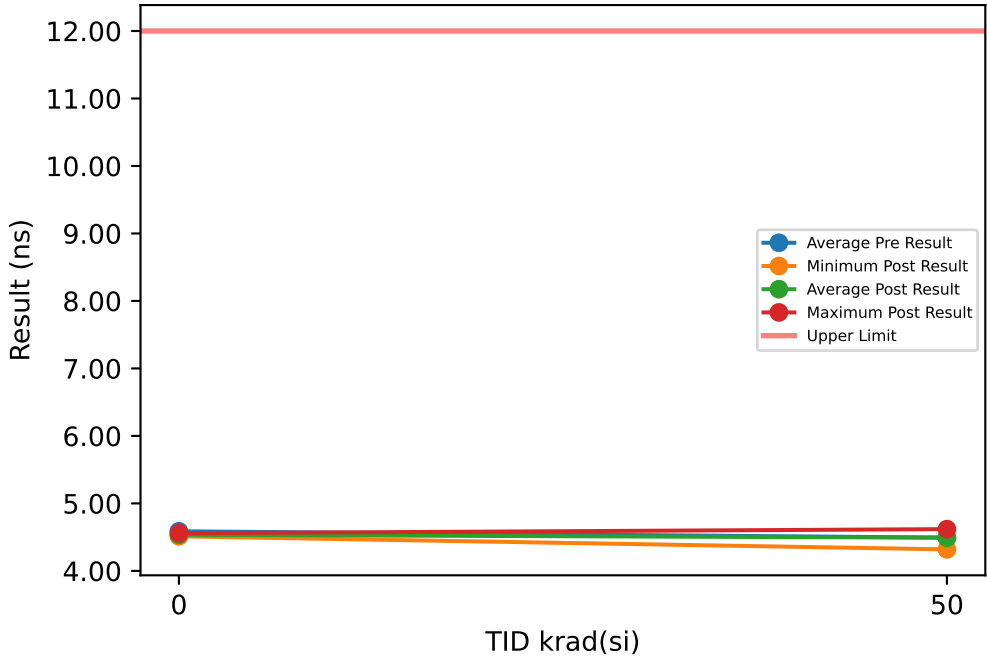
TID vs Post - Pre Exposure Delta



Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.977	5.0114	5.0457	0.048578	5.0431	5.0448	5.0464	0.0023335	-0.0026	0.0334	0.0694	0.050912
50	5.0071	5.0612	5.1044	0.029972	4.9651	5.0091	5.0902	0.043715	-0.1071	-0.05205	0.0388	0.048549

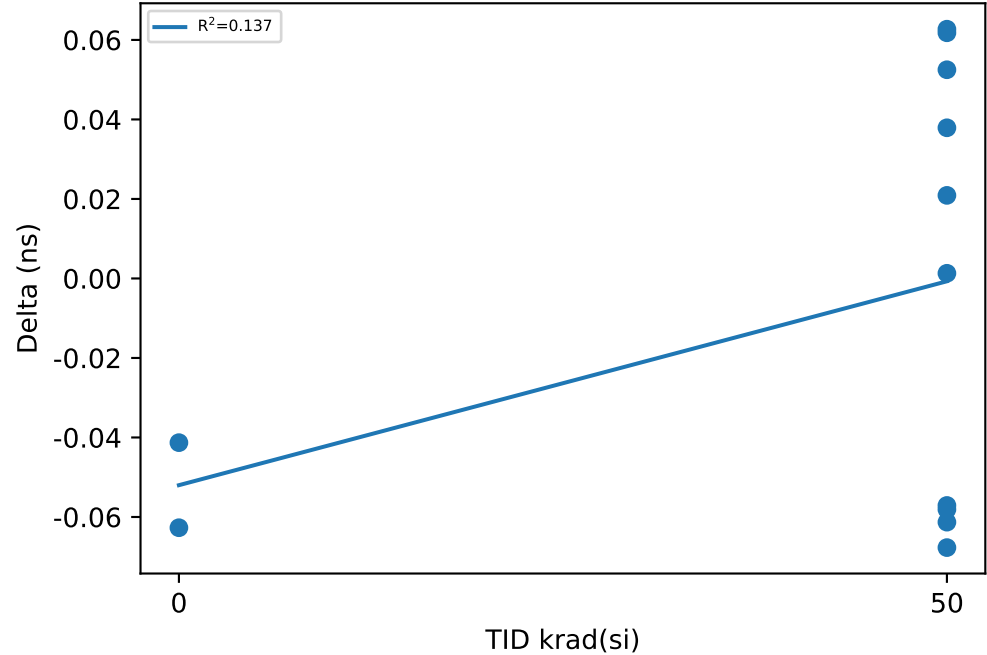
TID vs Result Stats



Test Results (Upper Limit = 12.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.5751	4.5125	-0.0627
2	0	Correlation	4.5988	4.5575	-0.0413
4	50	Bias	4.3768	4.3186	-0.0581
6	50	Bias	4.5736	4.506	-0.0677
7	50	Bias	4.45	4.4878	0.0379
8	50	Bias	4.4843	4.423	-0.0613
9	50	Bias	4.4108	4.4734	0.0627
11	50	Unbias	4.6018	4.5447	-0.0571
12	50	Unbias	4.5502	4.571	0.0209
13	50	Unbias	4.5126	4.5651	0.0525
14	50	Unbias	4.5571	4.6189	0.0618
15	50	Unbias	4.4135	4.4147	0.0013

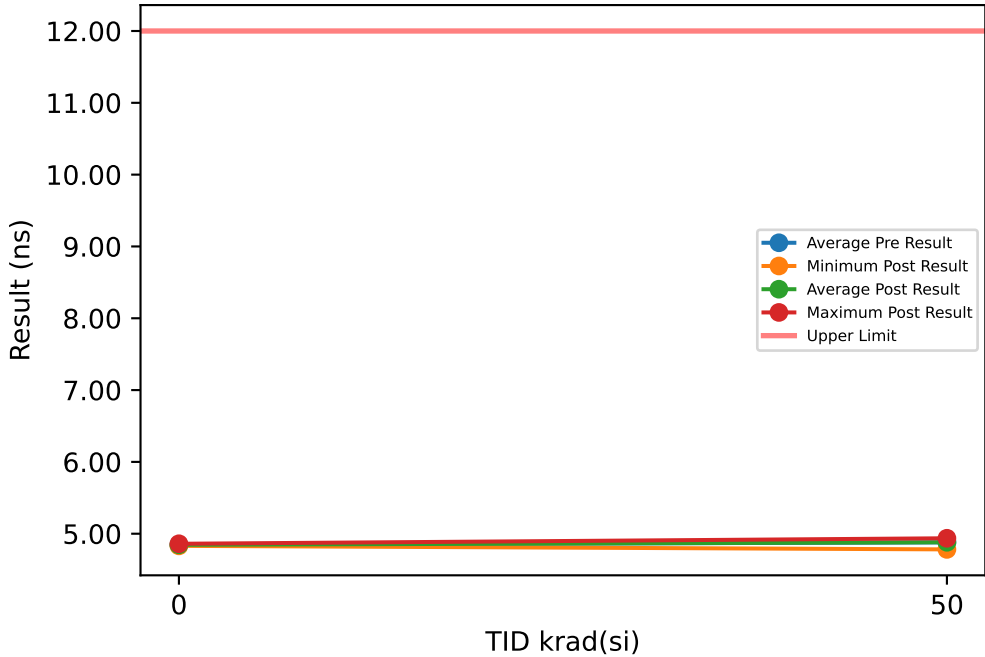
TID vs Post - Pre Exposure Delta



Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.5751	4.587	4.5988	0.016758	4.5125	4.535	4.5575	0.031891	-0.0627	-0.052	-0.0413	0.015132
50	4.3768	4.493	4.6018	0.077918	4.3186	4.4923	4.6189	0.089318	-0.0677	-0.00071	0.0627	0.05513

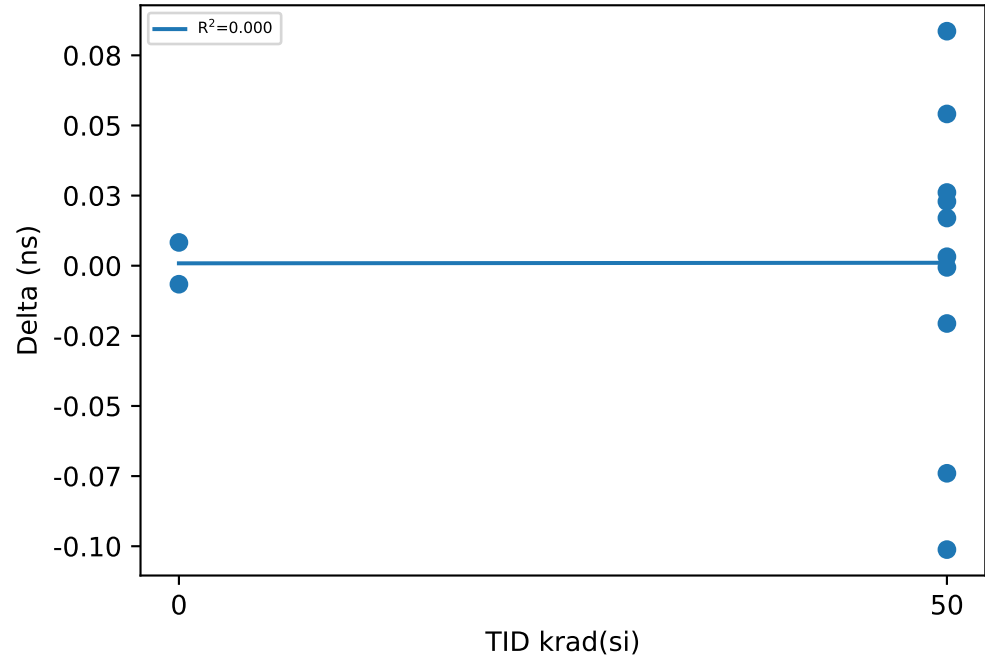
TID vs Result Stats



Test Results (Upper Limit = 12.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.8375	4.8309	-0.0066
2	0	Correlation	4.8518	4.8601	0.0083
4	50	Bias	4.8982	4.9211	0.0229
6	50	Bias	4.8344	4.8885	0.0541
7	50	Bias	4.8466	4.8636	0.017
8	50	Bias	4.8757	4.9018	0.0261
9	50	Bias	4.8994	4.9026	0.0032
11	50	Unbias	4.8829	4.7817	-0.1012
12	50	Unbias	4.9371	4.9365	-0.0006
13	50	Unbias	4.9002	4.8262	-0.074
14	50	Unbias	4.853	4.9366	0.0836
15	50	Unbias	4.8699	4.8493	-0.0206

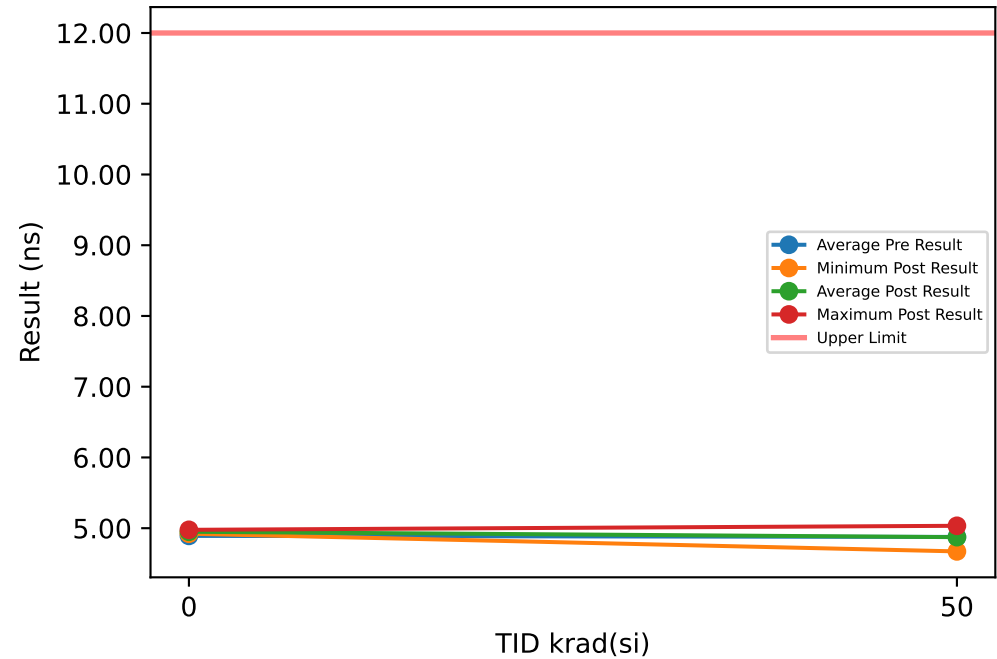
TID vs Post - Pre Exposure Delta



Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.8375	4.8446	4.8518	0.010112	4.8309	4.8455	4.8601	0.020648	-0.0066	0.00085	0.0083	0.010536
50	4.8344	4.8797	4.9371	0.030602	4.7817	4.8808	4.9366	0.050449	-0.1012	0.00105	0.0836	0.055329

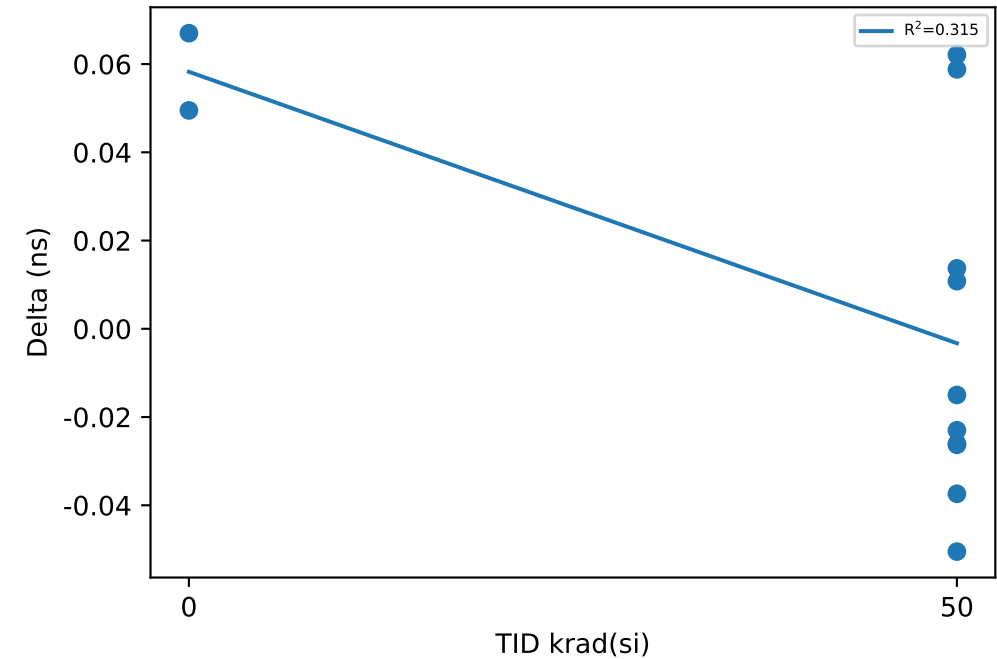
TID vs Result Stats



Test Results (Upper Limit = 12.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.9276	4.9771	0.0495
2	0	Correlation	4.8551	4.922	0.067
4	50	Bias	4.7095	4.672	-0.0374
6	50	Bias	4.9111	4.8848	-0.0263
7	50	Bias	4.9089	4.8829	-0.026
8	50	Bias	4.814	4.7989	-0.015
9	50	Bias	4.8347	4.8484	0.0137
11	50	Unbias	4.937	4.9139	-0.023
12	50	Unbias	4.9098	4.9687	0.0588
13	50	Unbias	4.9718	5.0339	0.0621
14	50	Unbias	4.93	4.9409	0.0108
15	50	Unbias	4.8399	4.7893	-0.0505

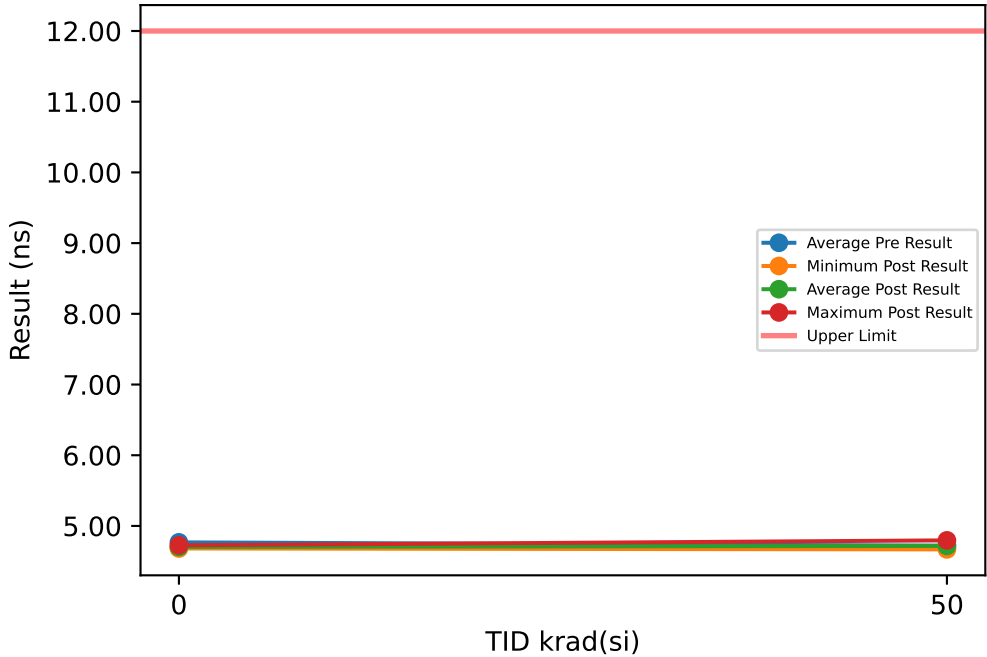
TID vs Post - Pre Exposure Delta



Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.8551	4.8913	4.9276	0.051265	4.922	4.9496	4.9771	0.038891	0.0495	0.05825	0.067	0.012374
50	4.7095	4.8766	4.9718	0.077353	4.672	4.8734	5.0339	0.10274	-0.0505	-0.00328	0.0621	0.038846

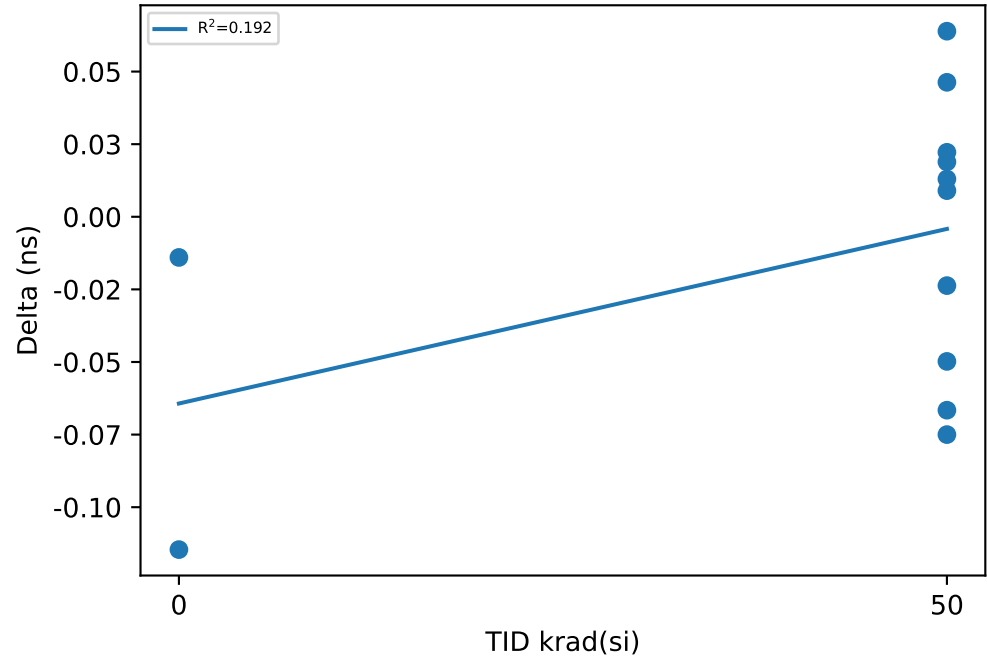
TID vs Result Stats



Test Results (Upper Limit = 12.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.796	4.6814	-0.1146
2	0	Correlation	4.7397	4.7257	-0.014
4	50	Bias	4.692	4.6683	-0.0237
6	50	Bias	4.74	4.6902	-0.0498
7	50	Bias	4.7282	4.7504	0.0222
8	50	Bias	4.753	4.6864	-0.0666
9	50	Bias	4.6693	4.6783	0.009
11	50	Unbias	4.7321	4.796	0.0639
12	50	Unbias	4.722	4.7683	0.0463
13	50	Unbias	4.7381	4.757	0.0189
14	50	Unbias	4.747	4.672	-0.075
15	50	Unbias	4.6902	4.7032	0.013

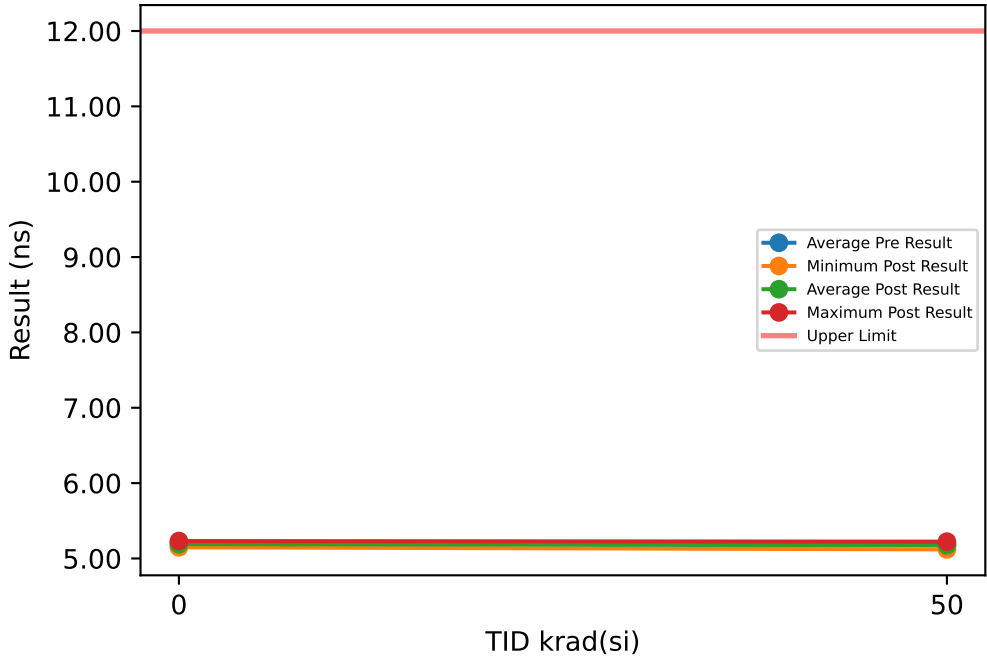
TID vs Post - Pre Exposure Delta



Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.7397	4.7679	4.796	0.03981	4.6814	4.7035	4.7257	0.031325	-0.1146	-0.0643	-0.014	0.071135
50	4.6693	4.7212	4.753	0.027872	4.6683	4.717	4.796	0.046341	-0.075	-0.00418	0.0639	0.047439

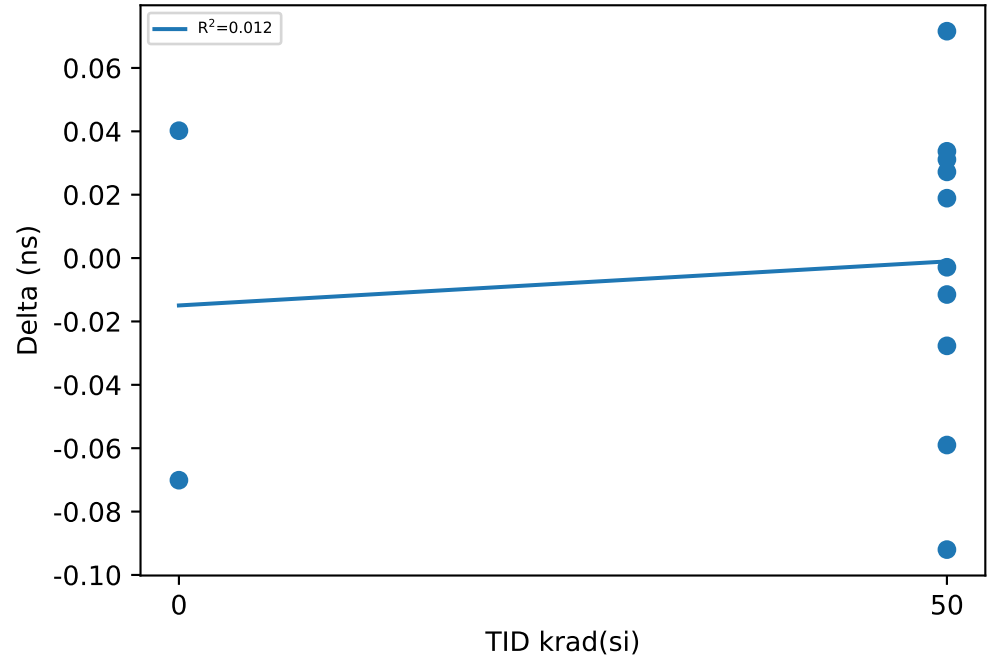
TID vs Result Stats



Test Results (Upper Limit = 12.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.1912	5.2313	0.0402
2	0	Correlation	5.218	5.1479	-0.0701
4	50	Bias	5.0931	5.1204	0.0272
6	50	Bias	5.167	5.1555	-0.0115
7	50	Bias	5.1567	5.1905	0.0337
8	50	Bias	5.1433	5.1405	-0.0029
9	50	Bias	5.1913	5.1323	-0.059
11	50	Unbias	5.1921	5.2232	0.0311
12	50	Unbias	5.2756	5.1837	-0.092
13	50	Unbias	5.1715	5.1903	0.0189
14	50	Unbias	5.2341	5.2065	-0.0277
15	50	Unbias	5.1428	5.2143	0.0716

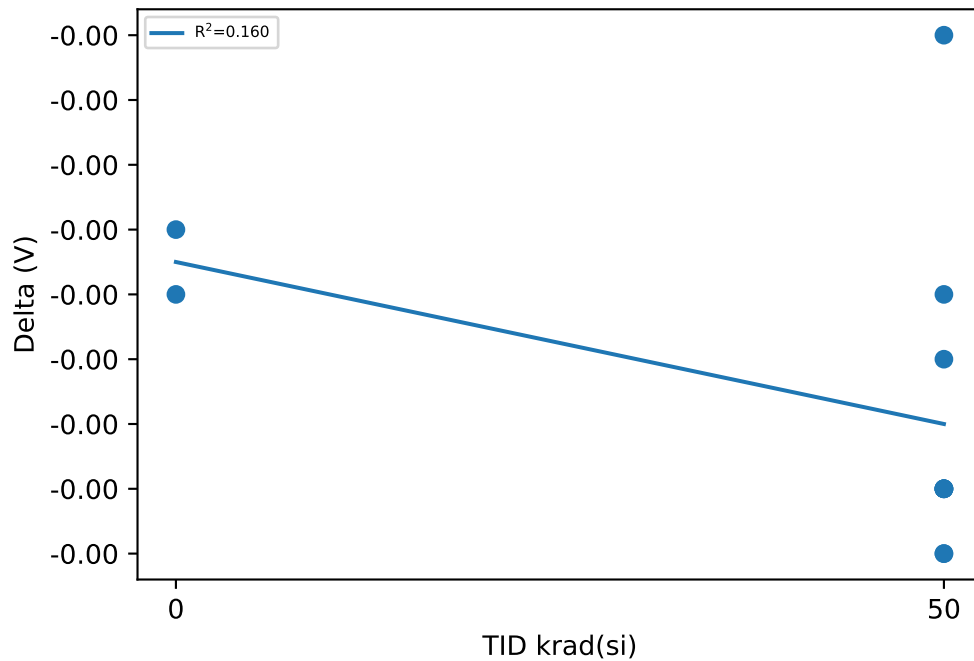
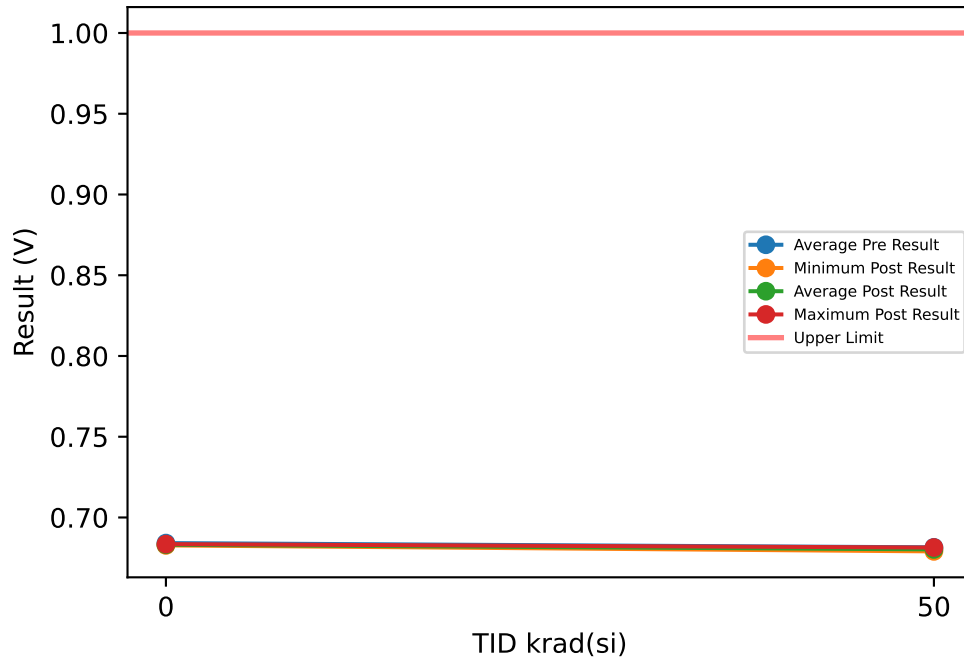
TID vs Post - Pre Exposure Delta



Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.1912	5.2046	5.218	0.019021	5.1479	5.1897	5.2313	0.058973	-0.0701	-0.01495	0.0402	0.077994
50	5.0931	5.1768	5.2756	0.050888	5.1204	5.1757	5.2232	0.036175	-0.092	-0.00106	0.0716	0.048498

Device Test: 24.29 OUT_CLAMP_0V(VOLTAGE|OUT_CLAMP/OUTL/0/0/0/0/0/0//@OUT_CLAMP_0V)



Test Results (Upper Limit = 1.0 (V))

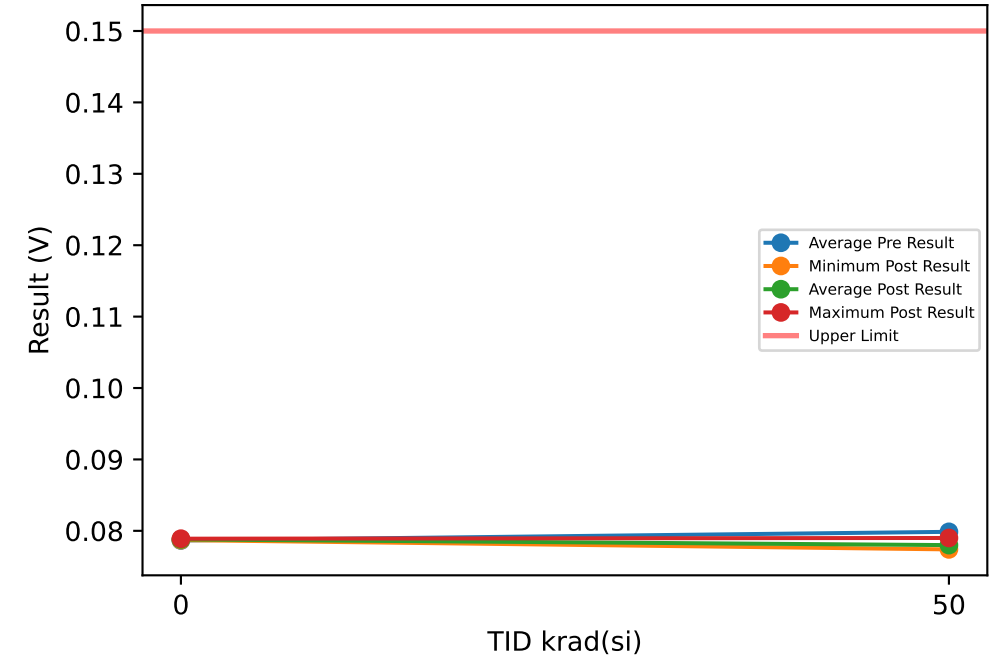
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.6845	0.6835	-0.001
2	0	Correlation	0.6838	0.6827	-0.0011
4	50	Bias	0.682	0.6809	-0.0011
6	50	Bias	0.6814	0.68	-0.0014
7	50	Bias	0.681	0.6796	-0.0014
8	50	Bias	0.6808	0.6794	-0.0014
9	50	Bias	0.681	0.6796	-0.0014
11	50	Unbias	0.6823	0.6809	-0.0014
12	50	Unbias	0.6824	0.6809	-0.0015
13	50	Unbias	0.6821	0.6806	-0.0015
14	50	Unbias	0.6802	0.679	-0.0012
15	50	Unbias	0.6821	0.6814	-0.0007

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6838	0.68415	0.6845	0.00049497	0.6827	0.6831	0.6835	0.00056569	-0.0011	-0.00105	-0.001	7.0711e-05
50	0.6802	0.68153	0.6824	0.00075285	0.679	0.68023	0.6814	0.00080973	-0.0015	-0.0013	-0.0007	0.00024495

Device Test: 24.3 OUT_VOL(LEVEL|LOW_LEVEL/OUTL/5/5/0/0/5/500kHz//@OUT_VOL)

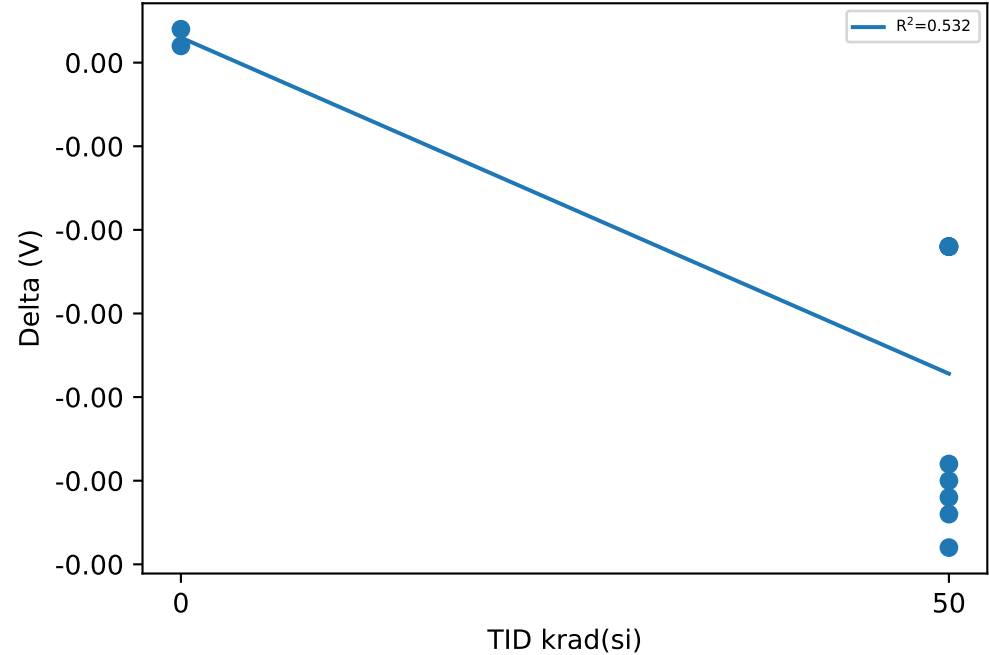
TID vs Result Stats



Test Results (Upper Limit = 0.15 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.0785	0.0787	0.0002
2	0	Correlation	0.0788	0.0789	0.0001
4	50	Bias	0.0807	0.078	-0.0027
6	50	Bias	0.0798	0.0774	-0.0024
7	50	Bias	0.08	0.0774	-0.0026
8	50	Bias	0.0805	0.0776	-0.0029
9	50	Bias	0.0803	0.0778	-0.0025
11	50	Unbias	0.0791	0.078	-0.0011
12	50	Unbias	0.0791	0.078	-0.0011
13	50	Unbias	0.079	0.0779	-0.0011
14	50	Unbias	0.08	0.0789	-0.0011
15	50	Unbias	0.0801	0.079	-0.0011

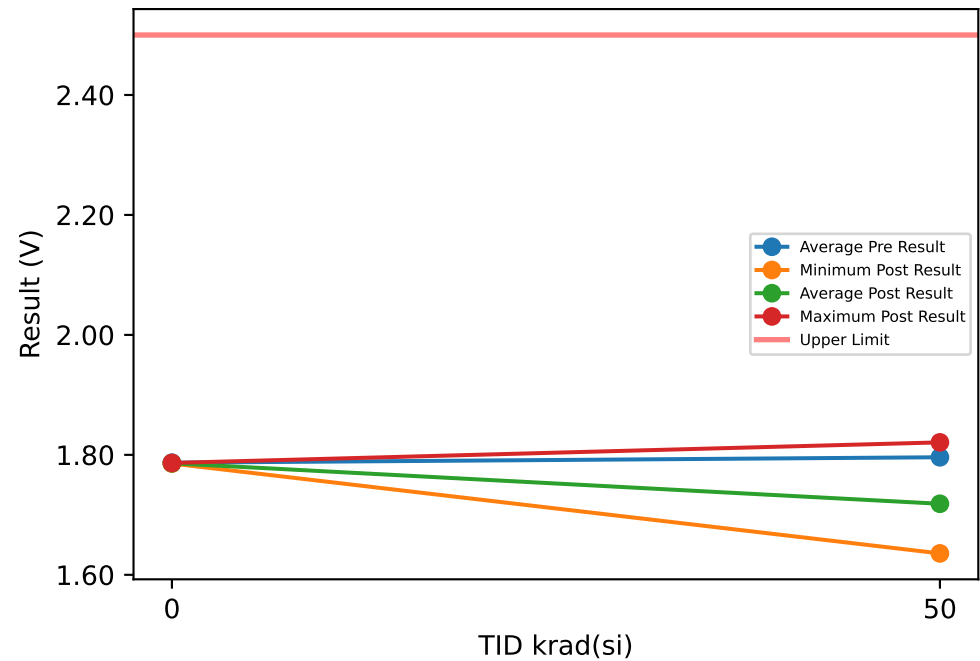
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0785	0.07865	0.0788	0.00021213	0.0787	0.0788	0.0789	0.00014142	0.0001	0.00015	0.0002	7.0711e-05
50	0.079	0.07986	0.0807	0.0006059	0.0774	0.078	0.079	0.00055176	-0.0029	-0.00186	-0.0011	0.00081131

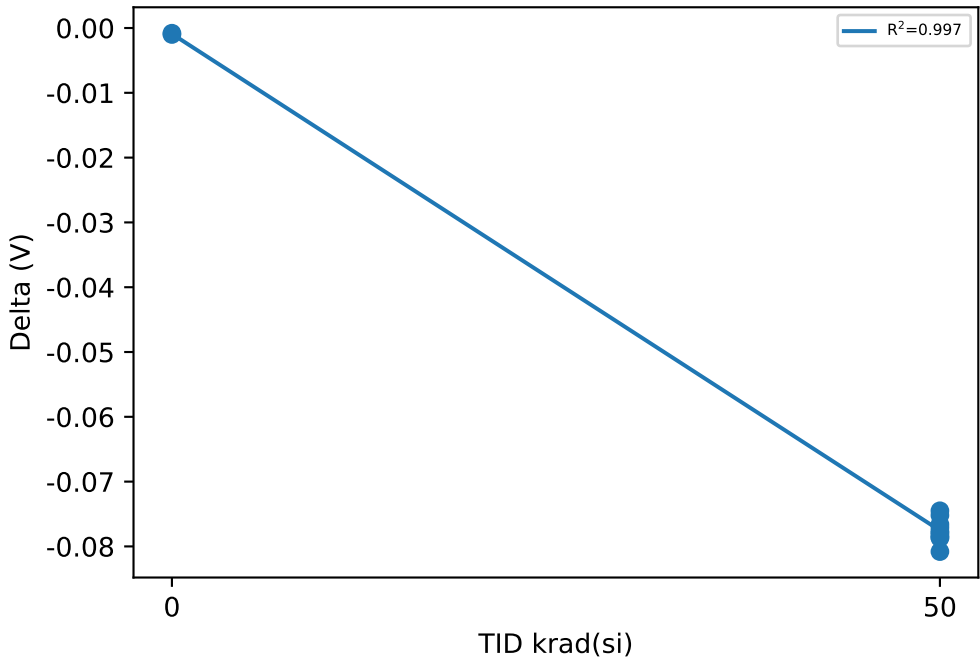
TID vs Result Stats



Test Results (Upper Limit = 2.5 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.7875	1.7865	-0.001
2	0	Correlation	1.7863	1.7855	-0.0008
4	50	Bias	1.8994	1.8208	-0.0786
6	50	Bias	1.7291	1.6546	-0.0745
7	50	Bias	1.7109	1.6357	-0.0752
8	50	Bias	1.8164	1.7381	-0.0783
9	50	Bias	1.8164	1.7393	-0.0771
11	50	Unbias	1.8121	1.7334	-0.0787
12	50	Unbias	1.8091	1.7325	-0.0766
13	50	Unbias	1.7717	1.6938	-0.0779
14	50	Unbias	1.7184	1.6376	-0.0808
15	50	Unbias	1.8763	1.7986	-0.0777

TID vs Post - Pre Exposure Delta

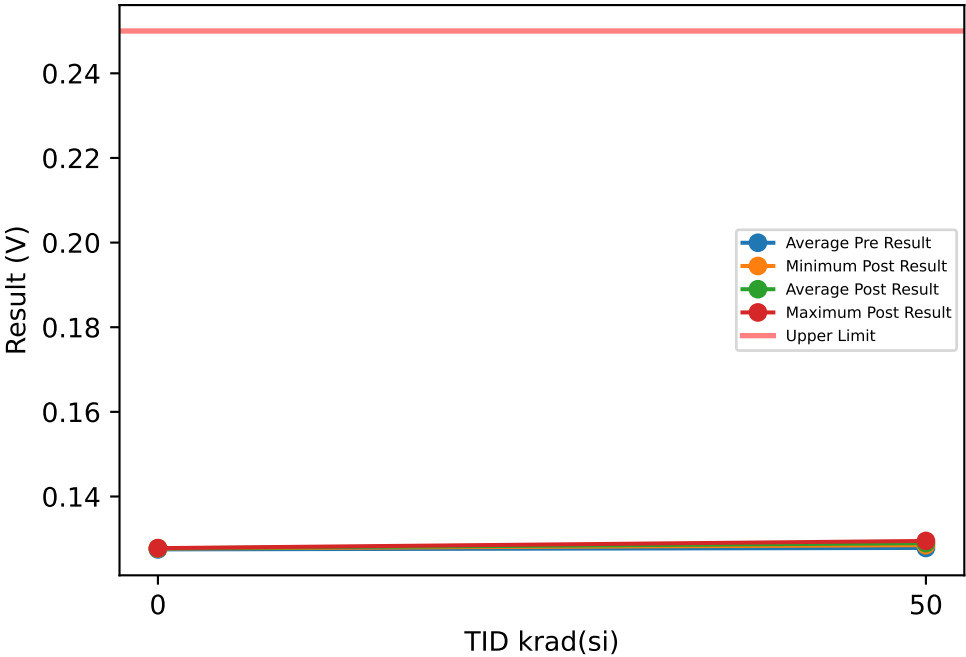


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.7863	1.7869	1.7875	0.00084853	1.7855	1.786	1.7865	0.00070711	-0.001	-0.0009	-0.0008	0.00014142
50	1.7109	1.796	1.8994	0.063886	1.6357	1.7184	1.8208	0.06343	-0.0808	-0.07754	-0.0745	0.0018143

Device Test: 24.4 OUT_VOH(LEVEL|HIGH_LEVEL/OUTH/5/5/0/0/5/500kHz//@OUT_VOH)

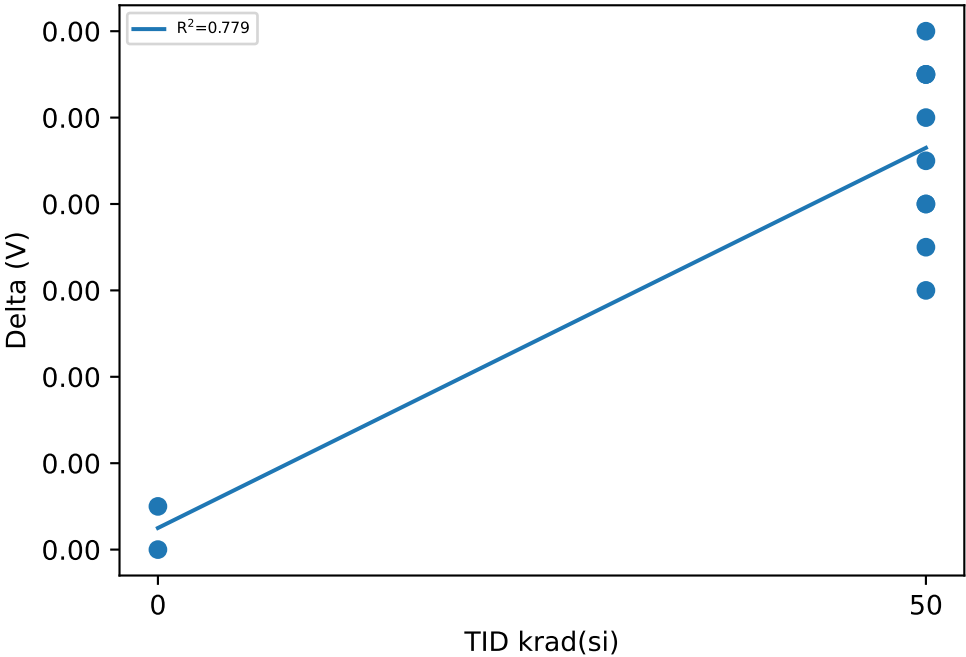
TID vs Result Stats



Test Results (Upper Limit = 0.25 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.1274	0.1277	0.0003
2	0	Correlation	0.1276	0.1278	0.0002
4	50	Bias	0.1274	0.1287	0.0013
6	50	Bias	0.1283	0.1295	0.0012
7	50	Bias	0.1276	0.129	0.0014
8	50	Bias	0.1278	0.1291	0.0013
9	50	Bias	0.1281	0.1294	0.0013
11	50	Unbias	0.1278	0.1287	0.0009
12	50	Unbias	0.1275	0.1285	0.001
13	50	Unbias	0.1278	0.1288	0.001
14	50	Unbias	0.1277	0.1288	0.0011
15	50	Unbias	0.1284	0.1292	0.0008

TID vs Post - Pre Exposure Delta

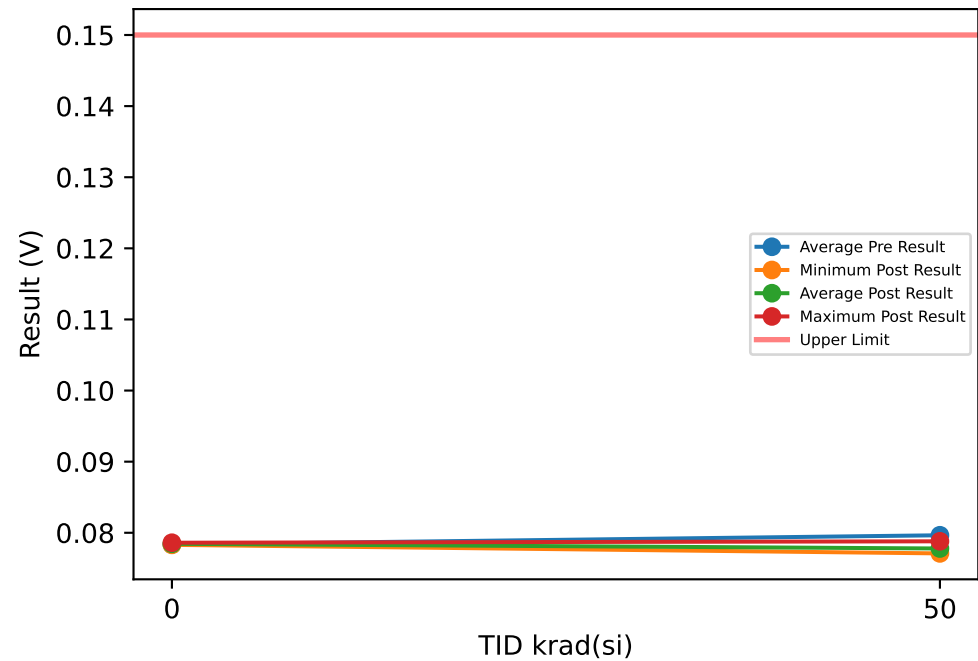


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1274	0.1275	0.1276	0.00014142	0.1277	0.12775	0.1278	7.0711e-05	0.0002	0.00025	0.0003	7.0711e-05
50	0.1274	0.12784	0.1284	0.00033066	0.1285	0.12897	0.1295	0.00032677	0.0008	0.00113	0.0014	0.00020028

Device Test: 24.5 OUT_VOL(LEVEL|LOW_LEVEL/OUTL/12/12/0/0/5/500kHz//@OUT_VOL)

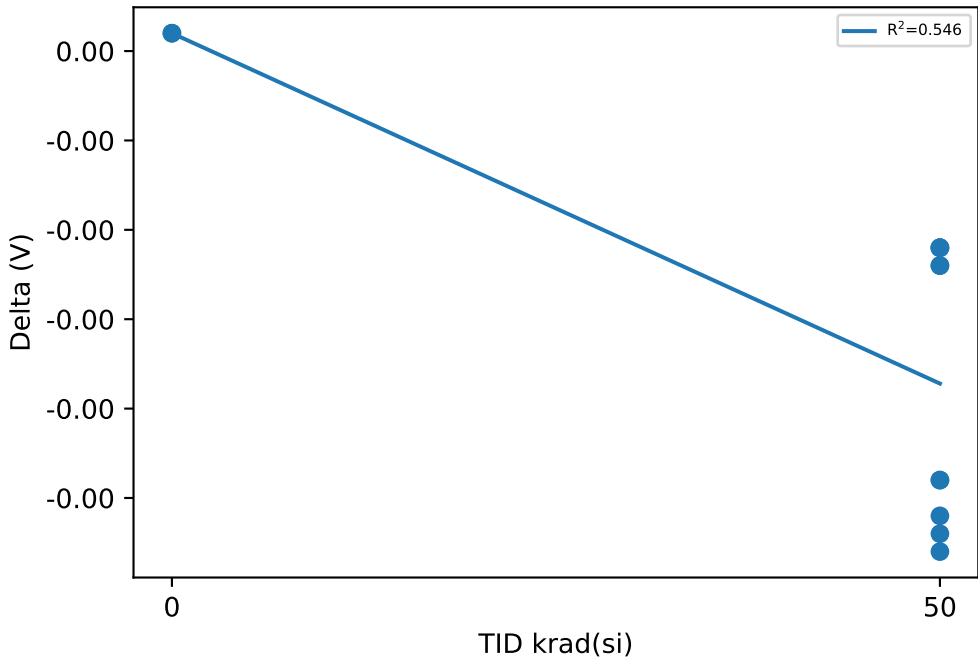
TID vs Result Stats



Test Results (Upper Limit = 0.15 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.0782	0.0783	0.0001
2	0	Correlation	0.0785	0.0786	0.0001
4	50	Bias	0.0805	0.0778	-0.0027
6	50	Bias	0.0795	0.0771	-0.0024
7	50	Bias	0.0797	0.0771	-0.0026
8	50	Bias	0.0802	0.0774	-0.0028
9	50	Bias	0.08	0.0776	-0.0024
11	50	Unbias	0.079	0.0779	-0.0011
12	50	Unbias	0.079	0.0778	-0.0012
13	50	Unbias	0.0788	0.0777	-0.0011
14	50	Unbias	0.0799	0.0787	-0.0012
15	50	Unbias	0.0799	0.0788	-0.0011

TID vs Post - Pre Exposure Delta

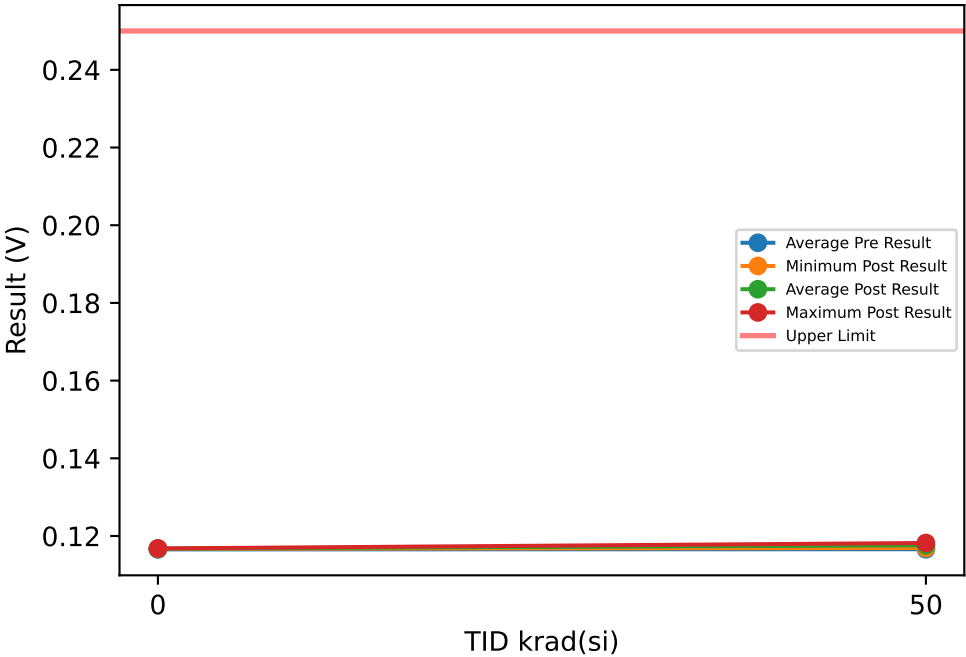


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0782	0.07835	0.0785	0.00021213	0.0783	0.07845	0.0786	0.00021213	0.0001	0.0001	0.0001	9.8131e-18
50	0.0788	0.07965	0.0805	0.00056421	0.0771	0.07779	0.0788	0.00057822	-0.0028	-0.00186	-0.0011	0.00076913

Device Test: 24.6 OUT_VOH(LEVEL|HIGH_LEVEL/OUTH/12/12/0/0/5/500kHz//@OUT_VOH)

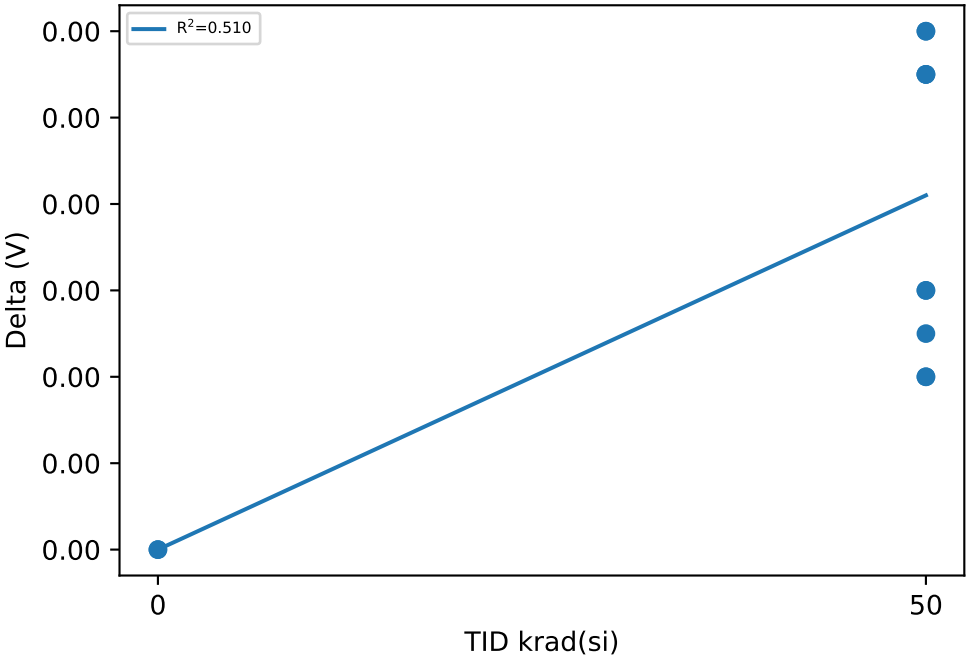
TID vs Result Stats



Test Results (Upper Limit = 0.25 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.1166	0.1168	0.0002
2	0	Correlation	0.1165	0.1167	0.0002
4	50	Bias	0.1159	0.1173	0.0014
6	50	Bias	0.1161	0.1174	0.0013
7	50	Bias	0.1166	0.1179	0.0013
8	50	Bias	0.1168	0.1182	0.0014
9	50	Bias	0.1165	0.1178	0.0013
11	50	Unbias	0.1162	0.1169	0.0007
12	50	Unbias	0.1166	0.1174	0.0008
13	50	Unbias	0.1172	0.1178	0.0006
14	50	Unbias	0.1167	0.1175	0.0008
15	50	Unbias	0.1173	0.1179	0.0006

TID vs Post - Pre Exposure Delta

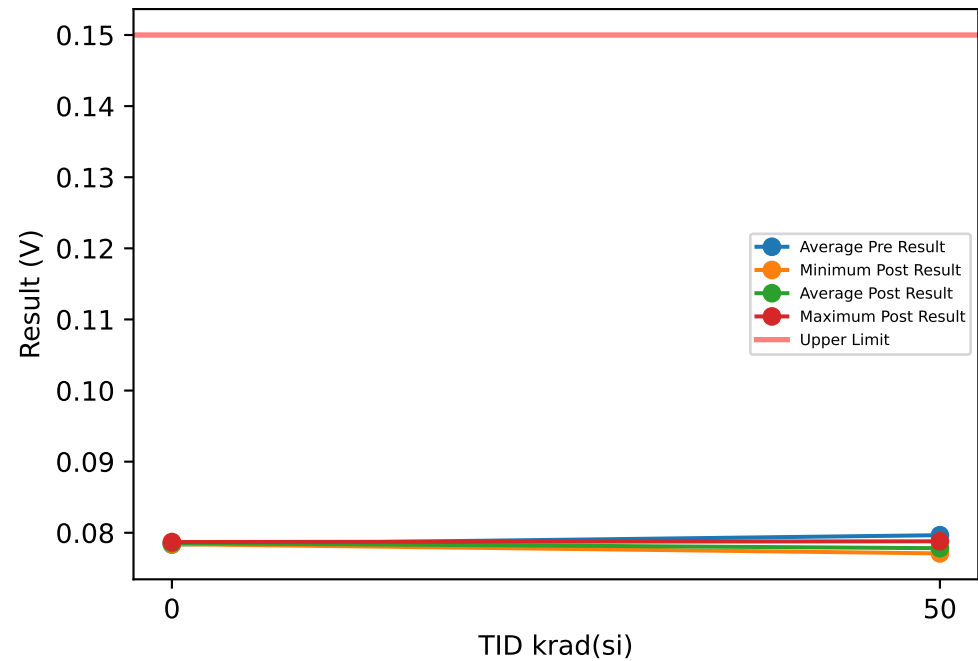


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1165	0.11655	0.1166	7.0711e-05	0.1167	0.11675	0.1168	7.0711e-05	0.0002	0.0002	0.0002	9.8131e-18
50	0.1159	0.11659	0.1173	0.00044833	0.1169	0.11761	0.1182	0.00037845	0.0006	0.00102	0.0014	0.00034577

Device Test: 24.7 OUT_VOL(LEVEL|LOW_LEVEL/OUTL/14/14/0/0/5/500kHz//@OUT_VOL)

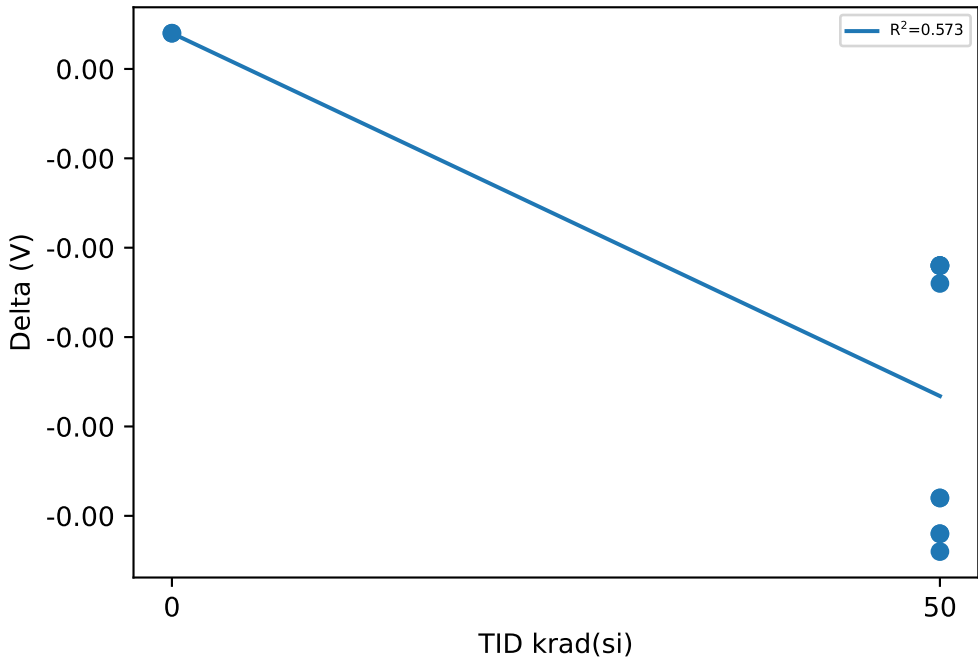
TID vs Result Stats



Test Results (Upper Limit = 0.15 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.0782	0.0784	0.0002
2	0	Correlation	0.0785	0.0787	0.0002
4	50	Bias	0.0805	0.0779	-0.0026
6	50	Bias	0.0795	0.0771	-0.0024
7	50	Bias	0.0798	0.0772	-0.0026
8	50	Bias	0.0802	0.0775	-0.0027
9	50	Bias	0.08	0.0776	-0.0024
11	50	Unbias	0.079	0.0779	-0.0011
12	50	Unbias	0.079	0.0778	-0.0012
13	50	Unbias	0.0788	0.0777	-0.0011
14	50	Unbias	0.0799	0.0788	-0.0011
15	50	Unbias	0.0799	0.0788	-0.0011

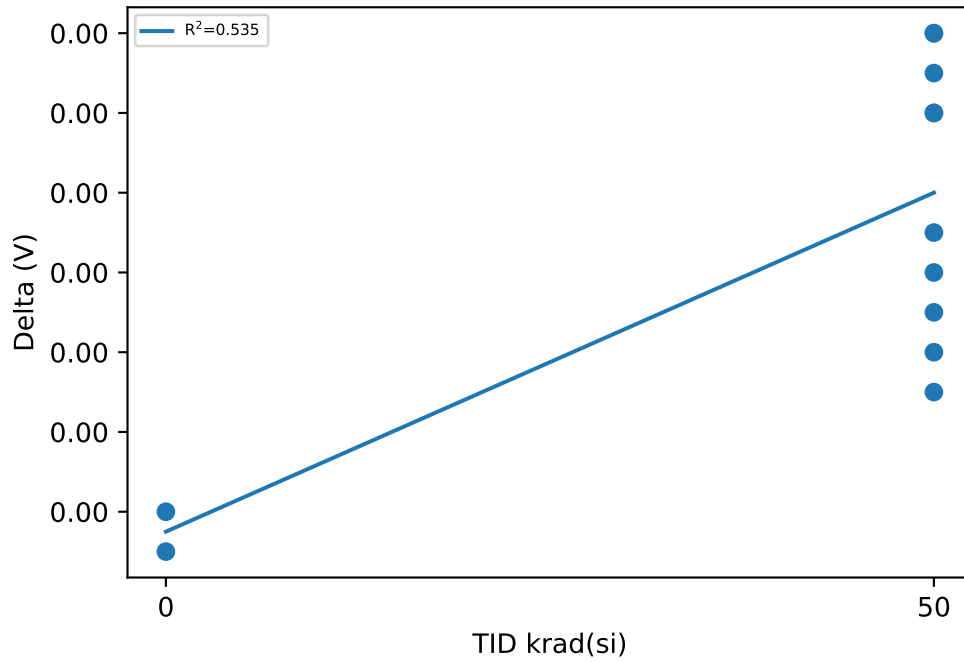
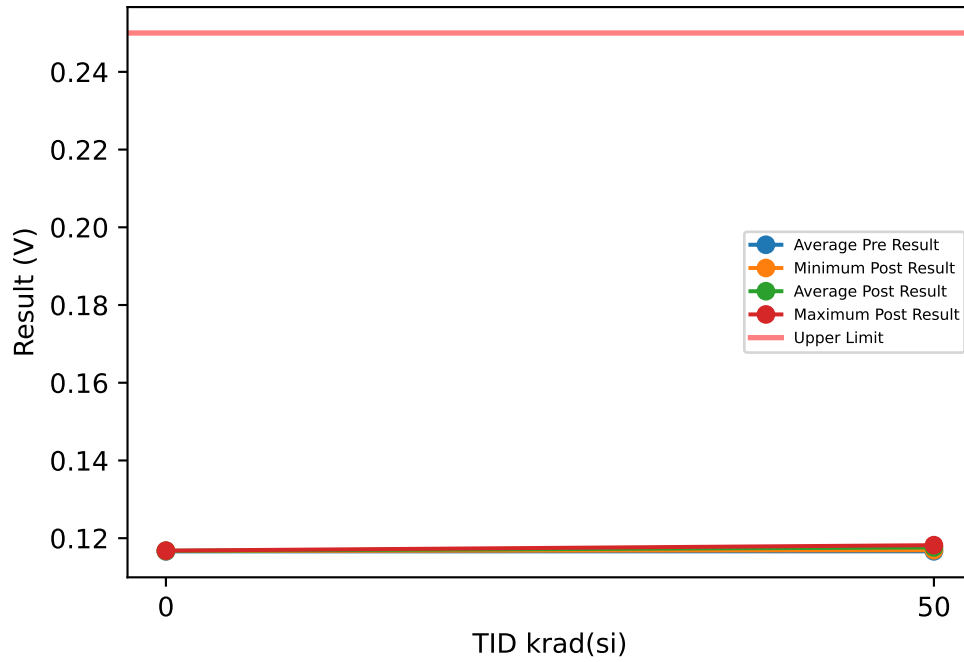
TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0782	0.07835	0.0785	0.00021213	0.0784	0.07855	0.0787	0.00021213	0.0002	0.0002	0.0002	9.8131e-18
50	0.0788	0.07966	0.0805	0.00056608	0.0771	0.07783	0.0788	0.00057745	-0.0027	-0.00183	-0.0011	0.00075432

Device Test: 24.8 OUT_VOH(LEVEL|HIGH_LEVEL/OUTH/14/14/0/0/5/500kHz//@OUT_VOH)



Test Results (Upper Limit = 0.25 (V))

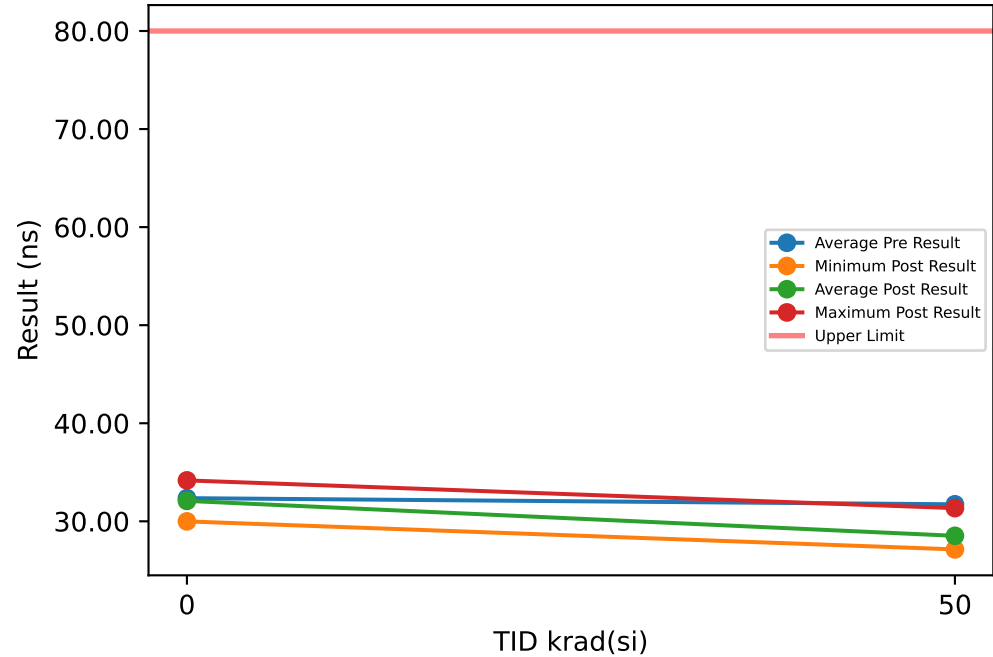
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.1166	0.1168	0.0002
2	0	Correlation	0.1166	0.1167	0.0001
4	50	Bias	0.116	0.1173	0.0013
6	50	Bias	0.1162	0.1174	0.0012
7	50	Bias	0.1166	0.118	0.0014
8	50	Bias	0.1168	0.1182	0.0014
9	50	Bias	0.1165	0.1177	0.0012
11	50	Unbias	0.1162	0.1169	0.0007
12	50	Unbias	0.1166	0.1174	0.0008
13	50	Unbias	0.1173	0.1178	0.0005
14	50	Unbias	0.1167	0.1176	0.0009
15	50	Unbias	0.1173	0.1179	0.0006

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1166	0.1166	0.1166	0	0.1167	0.11675	0.1168	7.0711e-05	0.0001	0.00015	0.0002	7.0711e-05
50	0.116	0.11662	0.1173	0.00043665	0.1169	0.11762	0.1182	0.00038239	0.0005	0.001	0.0014	0.00033993

Device Test: 25.1 T_LEB(TIMING|LEB/EN/5/5/0/0/5/500kHz//@T_LEB)

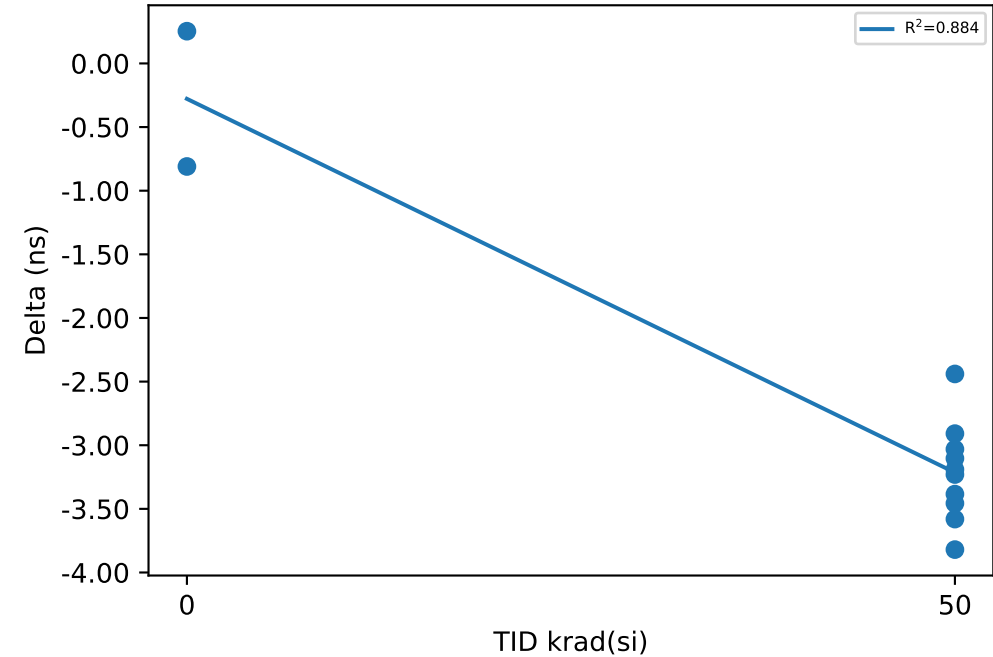
TID vs Result Stats



Test Results (Upper Limit = 80.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	34.982	34.173	-0.8097
2	0	Correlation	29.739	29.992	0.2533
4	50	Bias	32.617	29.16	-3.4566
6	50	Bias	30.527	27.297	-3.2302
7	50	Bias	32.351	28.531	-3.8201
8	50	Bias	34.448	31.344	-3.1036
9	50	Bias	31.539	27.958	-3.5804
11	50	Unbias	30.044	27.135	-2.9088
12	50	Unbias	32.242	29.051	-3.1908
13	50	Unbias	30.933	28.493	-2.4399
14	50	Unbias	30.495	27.464	-3.0312
15	50	Unbias	32.148	28.764	-3.384

TID vs Post - Pre Exposure Delta

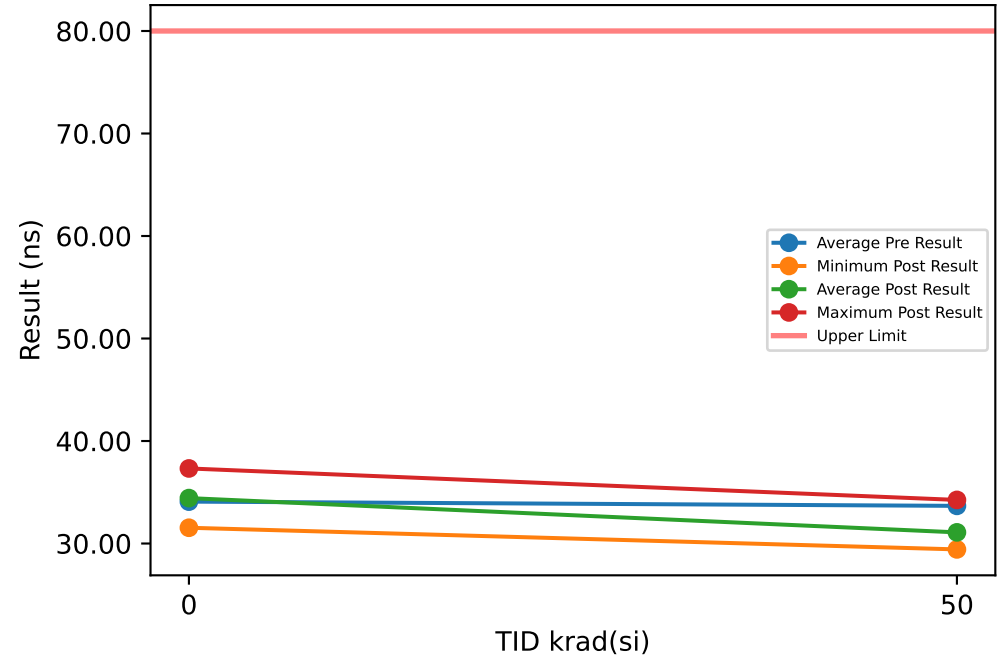


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	29.739	32.36	34.982	3.7079	29.992	32.082	34.173	2.9562	-0.8097	-0.2782	0.2533	0.75165
50	30.044	31.734	34.448	1.3116	27.135	28.52	31.344	1.2281	-3.8201	-3.2146	-2.4399	0.38415

Device Test: 25.4 T_LEB(TIMING|LEB/EN/12/12/0/0/5/500kHz//@T_LEB)

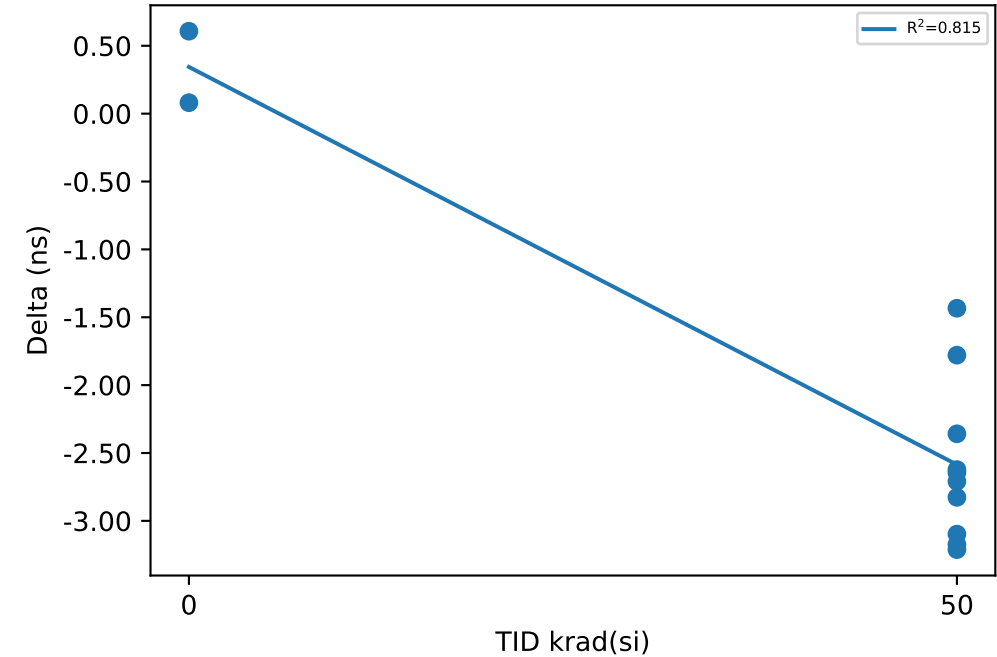
TID vs Result Stats



Test Results (Upper Limit = 80.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	36.717	37.324	0.6075
2	0	Correlation	31.458	31.539	0.0809
4	50	Bias	34.873	32.164	-2.7089
6	50	Bias	32.581	30.223	-2.3586
7	50	Bias	34.336	31.238	-3.0977
8	50	Bias	36.033	34.254	-1.7793
9	50	Bias	33.646	30.82	-2.8267
11	50	Unbias	32.072	29.427	-2.645
12	50	Unbias	34.387	31.213	-3.1735
13	50	Unbias	32.169	30.735	-1.4335
14	50	Unbias	32.203	29.581	-2.6223
15	50	Unbias	34.441	31.229	-3.2117

TID vs Post - Pre Exposure Delta

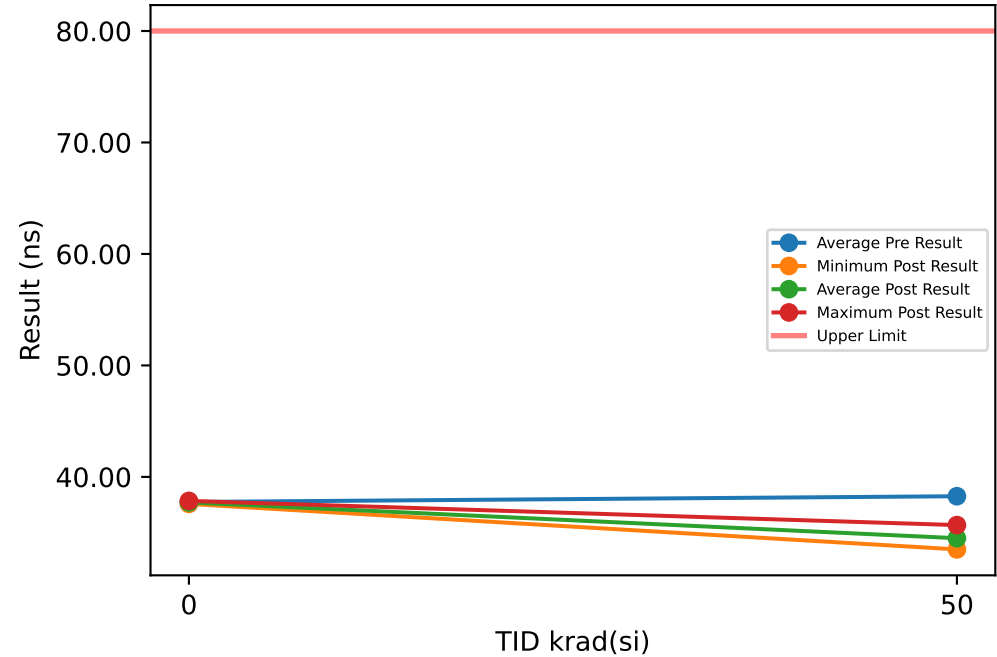


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	31.458	34.087	36.717	3.7185	31.539	34.431	37.324	4.0908	0.0809	0.3442	0.6075	0.37236
50	32.072	33.674	36.033	1.3633	29.427	31.088	34.254	1.3829	-3.2117	-2.5857	-1.4335	0.58756

Device Test: 25.7 T_LEB(TIMING|LEB/EN/14/14/0/0/5/500kHz//@T_LEB)

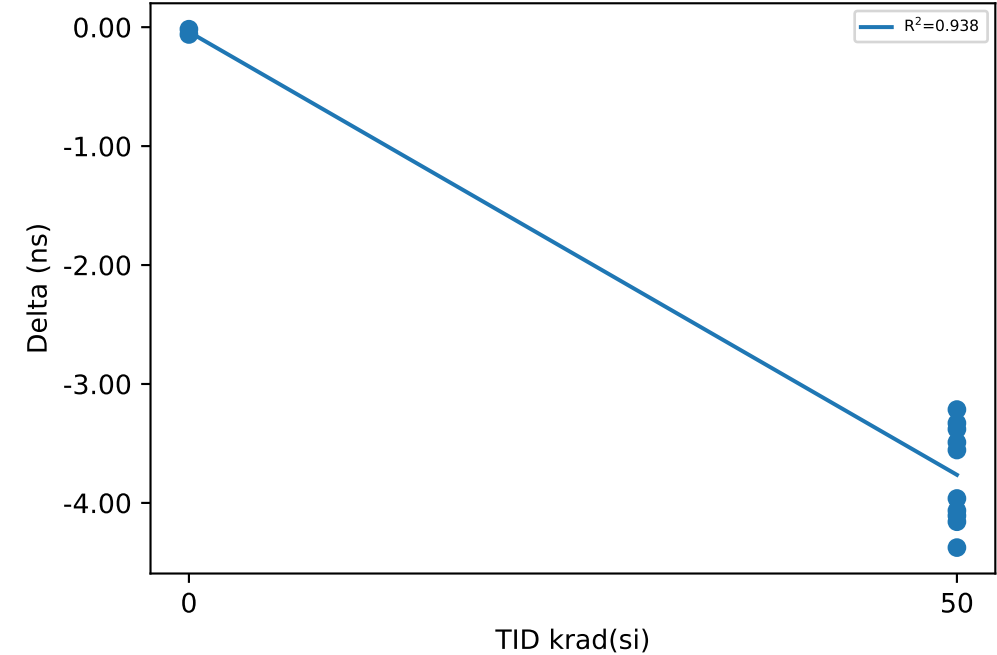
TID vs Result Stats



Test Results (Upper Limit = 80.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	37.907	37.846	-0.0614
2	0	Correlation	37.597	37.58	-0.017
4	50	Bias	38.617	35.288	-3.329
6	50	Bias	37.661	34.446	-3.215
7	50	Bias	39.058	35.678	-3.3802
8	50	Bias	38.59	35.099	-3.4908
9	50	Bias	38.559	35.004	-3.5554
11	50	Unbias	37.572	33.609	-3.9627
12	50	Unbias	38.666	34.602	-4.0645
13	50	Unbias	37.604	33.497	-4.1072
14	50	Unbias	38.126	33.968	-4.1583
15	50	Unbias	38.199	33.823	-4.3757

TID vs Post - Pre Exposure Delta

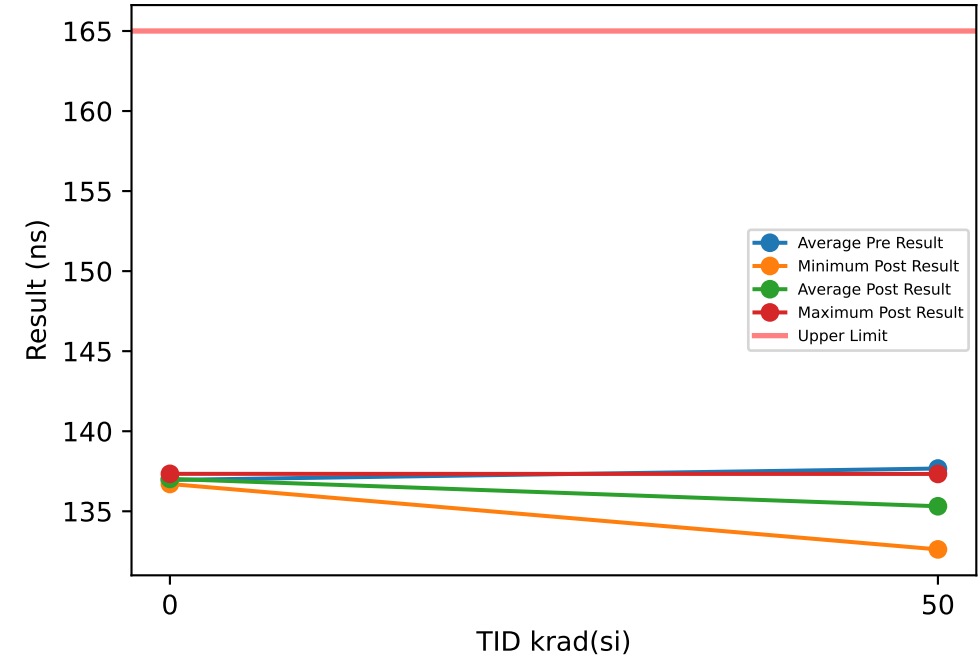


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	37.597	37.752	37.907	0.2197	37.58	37.713	37.846	0.1883	-0.0614	-0.0392	-0.017	0.031396
50	37.572	38.265	39.058	0.51775	33.497	34.501	35.678	0.75848	-4.3757	-3.7639	-3.215	0.41275

Device Test: 26.1 TON_MIN(TIMING|MIN/OUT/4.5/4.5/0/0/4.5/500kHz//@TON_MIN)

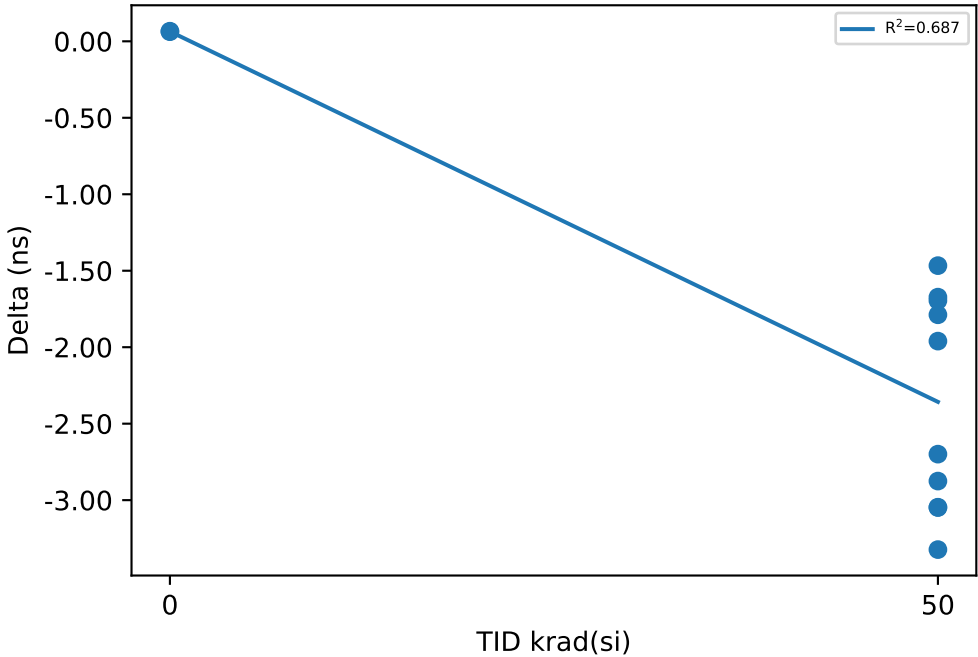
TID vs Result Stats



Test Results (Upper Limit = 165.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	136.64	136.71	0.0661
2	0	Correlation	137.27	137.34	0.0629
4	50	Bias	138.04	136.37	-1.6727
6	50	Bias	137.31	135.85	-1.4667
7	50	Bias	139.12	137.33	-1.788
8	50	Bias	137.98	136.29	-1.6951
9	50	Bias	138.84	136.88	-1.9602
11	50	Unbias	136.51	133.64	-2.8753
12	50	Unbias	137.72	135.02	-2.6992
13	50	Unbias	136.84	133.51	-3.3233
14	50	Unbias	138.67	135.63	-3.0482
15	50	Unbias	135.67	132.62	-3.0462

TID vs Post - Pre Exposure Delta

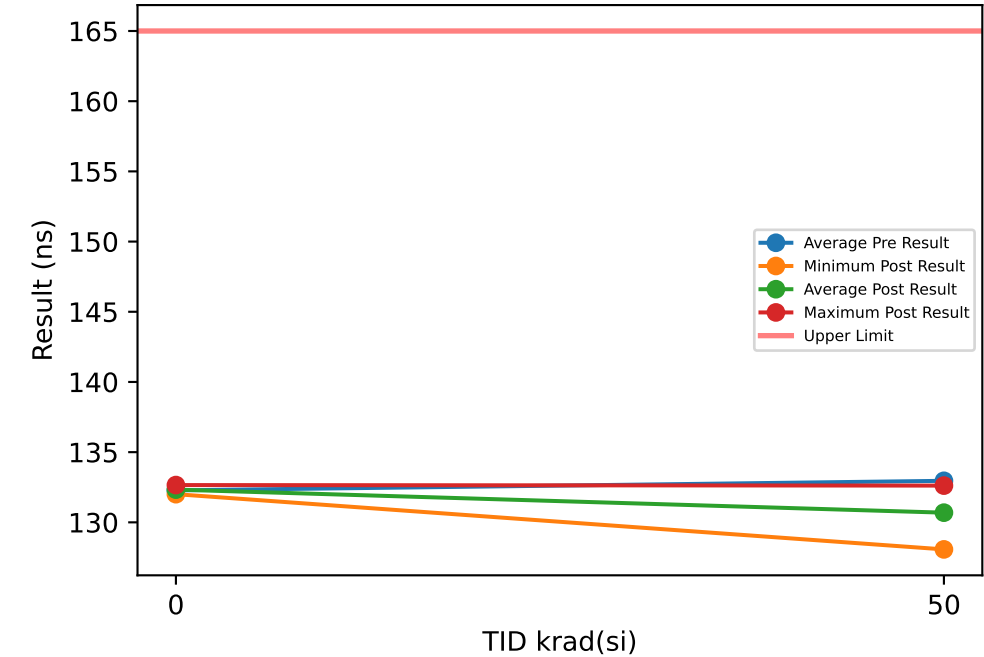


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	136.64	136.96	137.27	0.4488	136.71	137.02	137.34	0.44654	0.0629	0.0645	0.0661	0.0022627
50	135.67	137.67	139.12	1.1008	132.62	135.31	137.33	1.577	-3.3233	-2.3575	-1.4667	0.70336

Device Test: 26.2 TON_MIN(TIMING|MIN/OUT/5/5/0/0/5/500kHz//@TON_MIN)

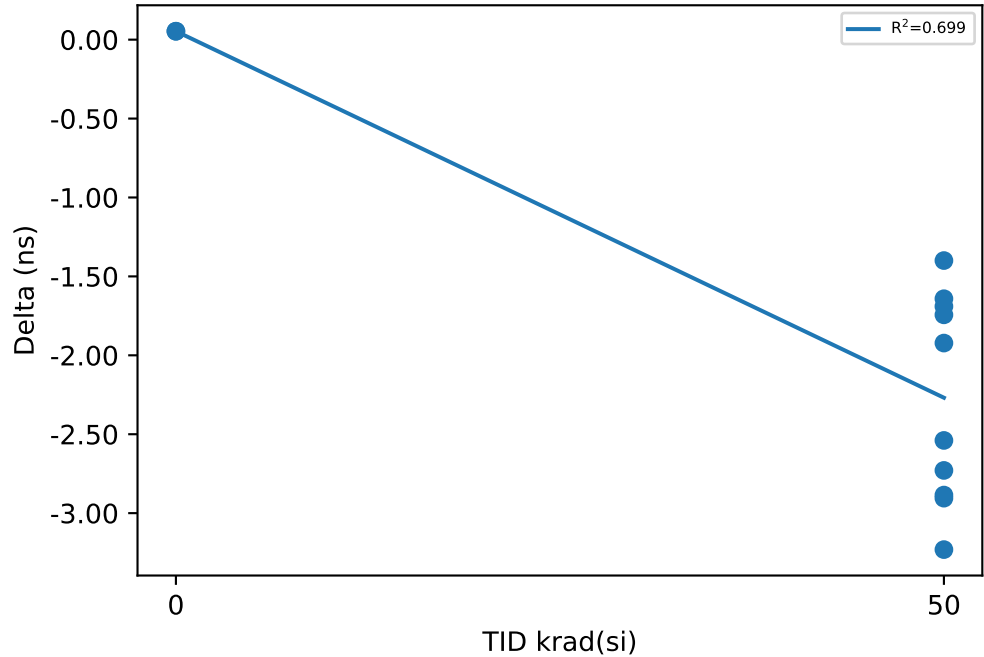
TID vs Result Stats



Test Results (Upper Limit = 165.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	131.95	132.01	0.0536
2	0	Correlation	132.6	132.66	0.0533
4	50	Bias	133.22	131.58	-1.6415
6	50	Bias	132.6	131.2	-1.3996
7	50	Bias	134.36	132.62	-1.7435
8	50	Bias	133.24	131.55	-1.69
9	50	Bias	134.08	132.15	-1.9224
11	50	Unbias	131.86	129.13	-2.7293
12	50	Unbias	133.08	130.54	-2.5393
13	50	Unbias	132.23	129	-3.231
14	50	Unbias	133.93	131.05	-2.8855
15	50	Unbias	130.98	128.07	-2.9051

TID vs Post - Pre Exposure Delta

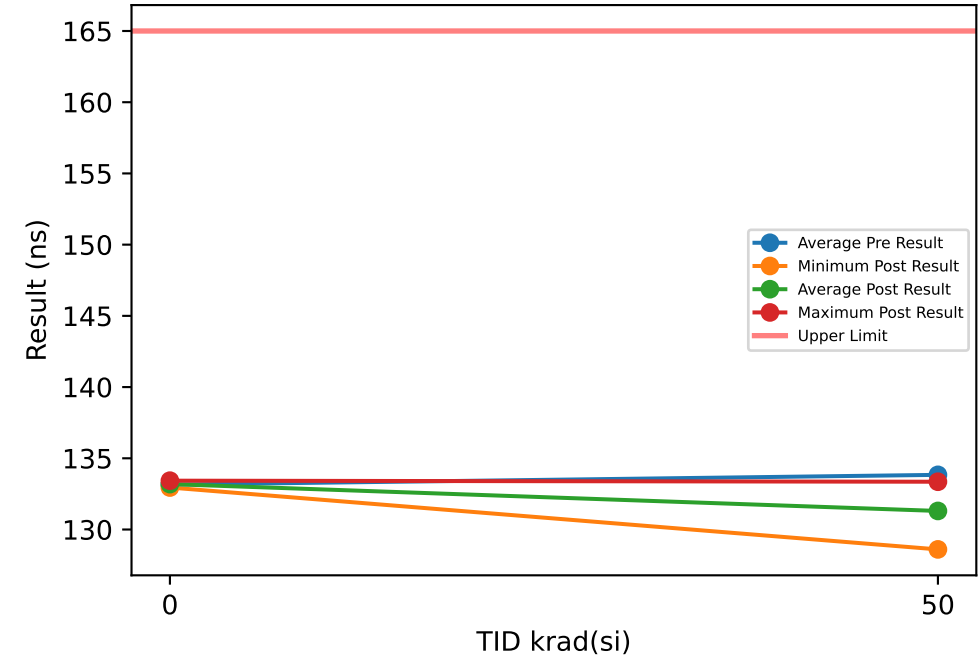


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	131.95	132.28	132.6	0.4587	132.01	132.33	132.66	0.45849	0.0533	0.05345	0.0536	0.00021213
50	130.98	132.96	134.36	1.0601	128.07	130.69	132.62	1.4881	-3.231	-2.2687	-1.3996	0.65627

Device Test: 26.3 TON_MIN(TIMING|MIN/OUT/12/12/0/0/5/500kHz//@TON_MIN)

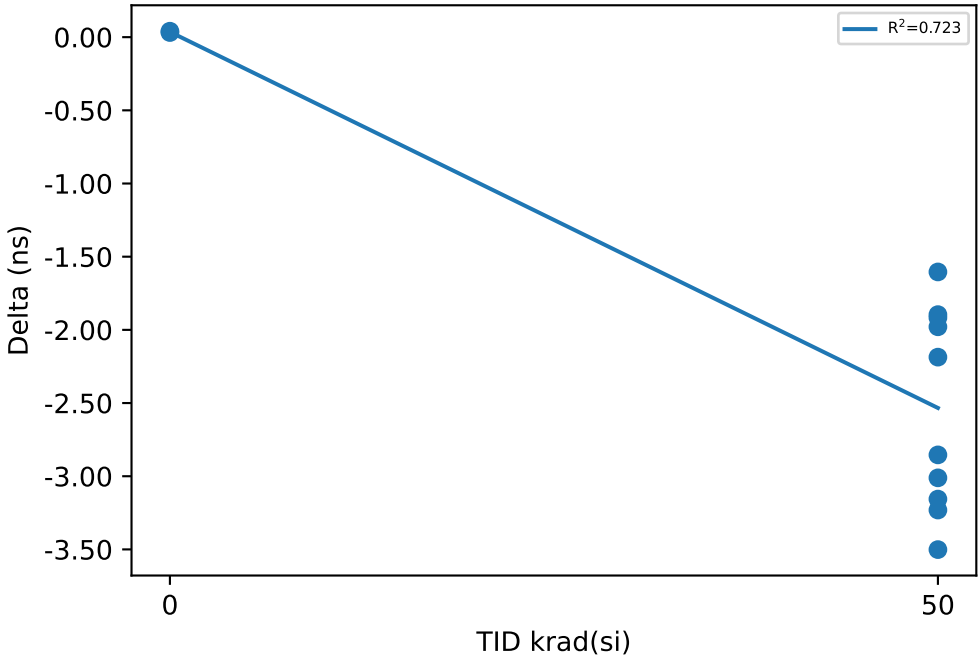
TID vs Result Stats



Test Results (Upper Limit = 165.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	132.91	132.95	0.0407
2	0	Correlation	133.4	133.43	0.0316
4	50	Bias	134.16	132.24	-1.9168
6	50	Bias	133.15	131.55	-1.6042
7	50	Bias	135.33	133.35	-1.979
8	50	Bias	134.05	132.16	-1.8958
9	50	Bias	134.98	132.8	-2.1863
11	50	Unbias	132.68	129.67	-3.0111
12	50	Unbias	134.26	131.41	-2.8542
13	50	Unbias	133.07	129.56	-3.5013
14	50	Unbias	134.85	131.69	-3.1561
15	50	Unbias	131.83	128.6	-3.231

TID vs Post - Pre Exposure Delta

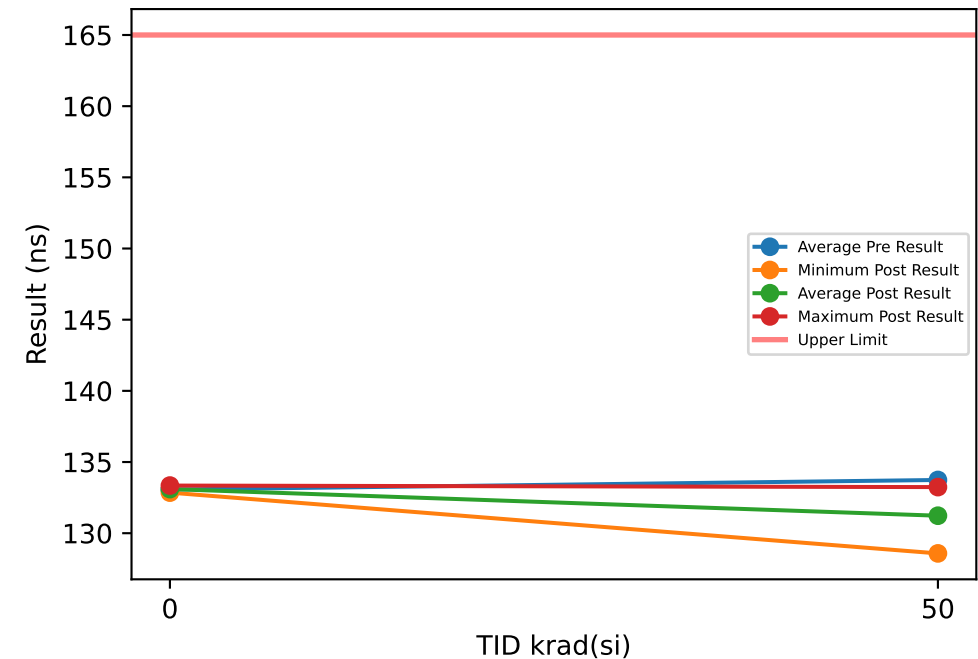


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	132.91	133.15	133.4	0.34641	132.95	133.19	133.43	0.33998	0.0316	0.03615	0.0407	0.0064347
50	131.83	133.84	135.33	1.1208	128.6	131.3	133.35	1.5359	-3.5013	-2.5336	-1.6042	0.68478

Device Test: 26.4 TON_MIN(TIMING|MIN/OUT/14/14/0/0/5/500kHz//@TON_MIN)

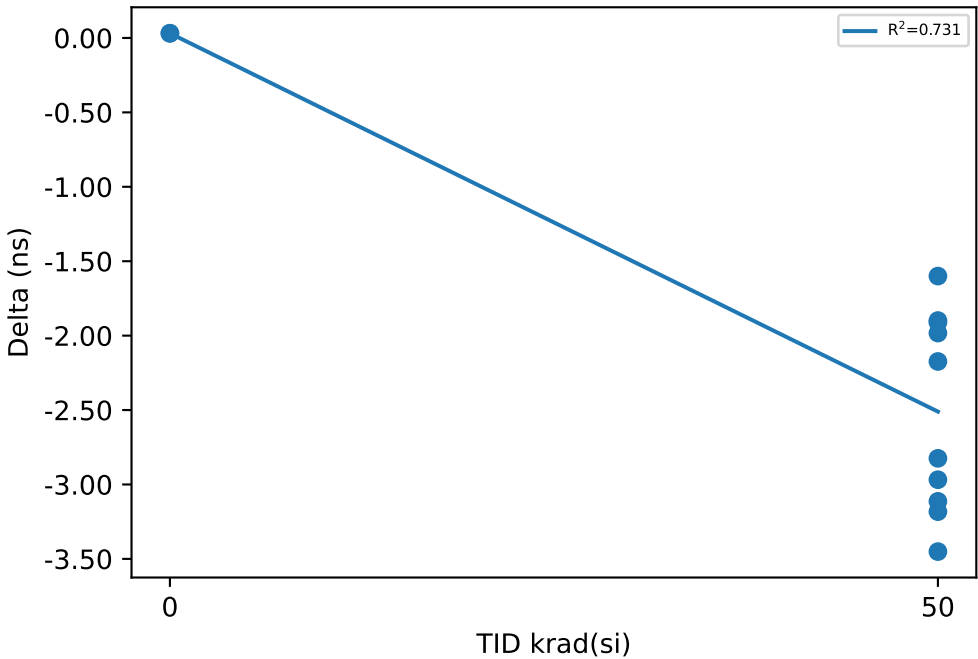
TID vs Result Stats



Test Results (Upper Limit = 165.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	132.82	132.85	0.0312
2	0	Correlation	133.32	133.35	0.032
4	50	Bias	134.06	132.15	-1.9109
6	50	Bias	133.07	131.47	-1.5998
7	50	Bias	135.22	133.24	-1.9827
8	50	Bias	133.97	132.07	-1.8987
9	50	Bias	134.87	132.69	-2.1736
11	50	Unbias	132.6	129.63	-2.968
12	50	Unbias	134.15	131.32	-2.8243
13	50	Unbias	132.96	129.51	-3.451
14	50	Unbias	134.74	131.63	-3.1133
15	50	Unbias	131.76	128.58	-3.1825

TID vs Post - Pre Exposure Delta

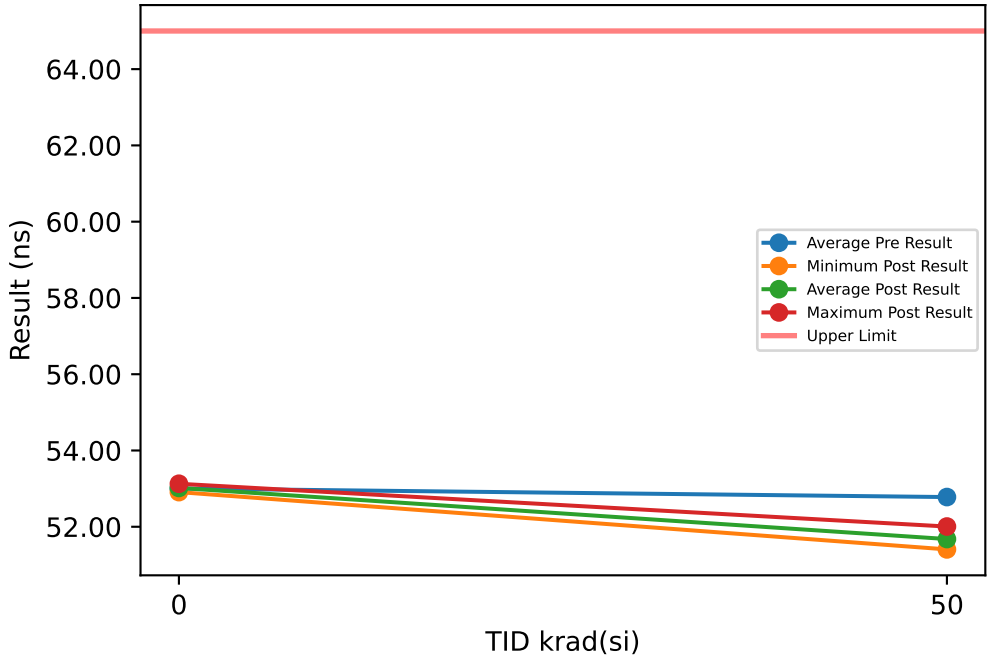


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	132.82	133.07	133.32	0.3508	132.85	133.1	133.35	0.35136	0.0312	0.0316	0.032	0.00056569
50	131.76	133.74	135.22	1.1092	128.58	131.23	133.24	1.5093	-3.451	-2.5105	-1.5998	0.66354

Device Test: 26.5 T_OFF_EXTENDER(TIMING|EXT/OUT/4.5/4.5/0/0/4.5/500kHz//@T_OFF_EXTENDER)

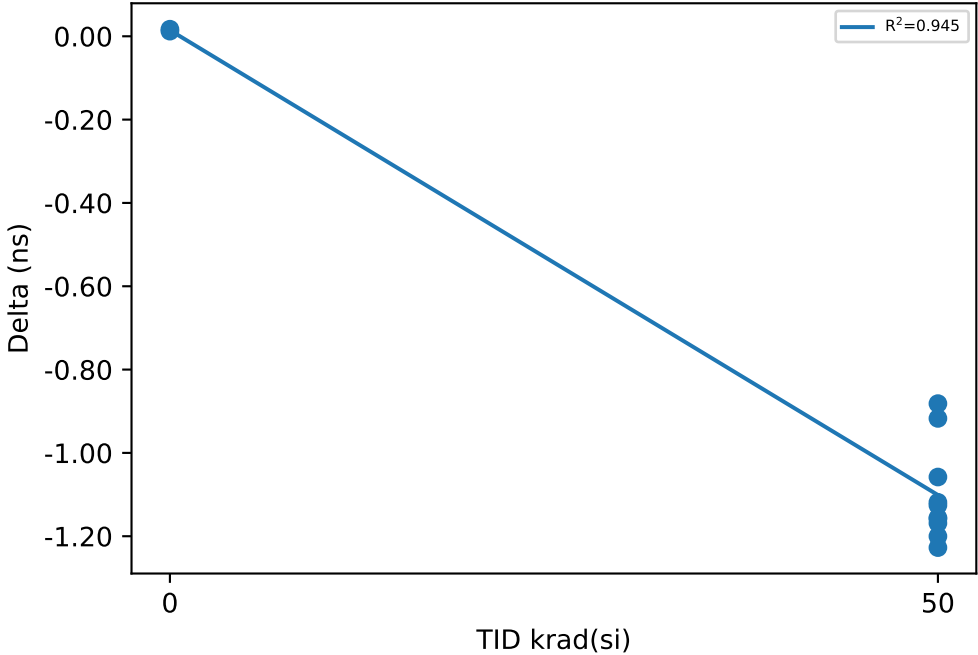
TID vs Result Stats



Test Results (Upper Limit = 65.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	52.896	52.909	0.0123
2	0	Correlation	53.111	53.128	0.017
4	50	Bias	52.462	51.545	-0.9172
6	50	Bias	52.462	51.581	-0.8817
7	50	Bias	52.74	51.572	-1.1686
8	50	Bias	52.464	51.406	-1.0579
9	50	Bias	52.873	51.673	-1.2002
11	50	Unbias	53.161	51.934	-1.2273
12	50	Unbias	53.162	52.006	-1.1557
13	50	Unbias	52.783	51.625	-1.1581
14	50	Unbias	52.733	51.607	-1.1257
15	50	Unbias	52.949	51.831	-1.1186

TID vs Post - Pre Exposure Delta

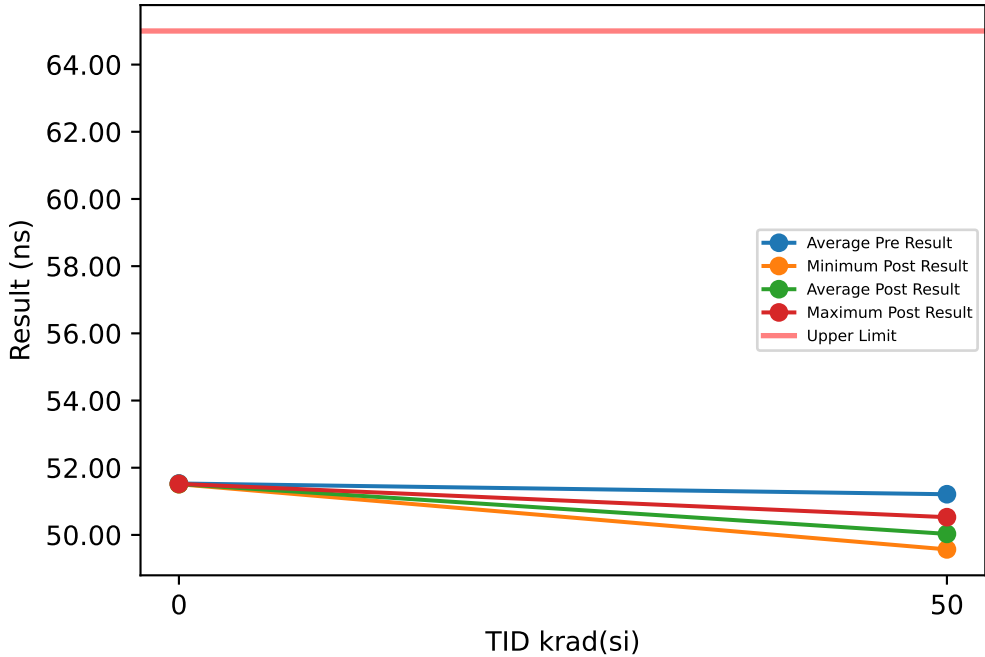


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52.896	53.003	53.111	0.15153	52.909	53.018	53.128	0.15486	0.0123	0.01465	0.017	0.0033234
50	52.462	52.779	53.162	0.26533	51.406	51.678	52.006	0.18753	-1.2273	-1.1011	-0.8817	0.11608

Device Test: 26.7 T_OFF_EXTENDER(TIMING|EXT/OUT/14/14/0/0/5/500kHz//@T_OFF_EXTENDER)

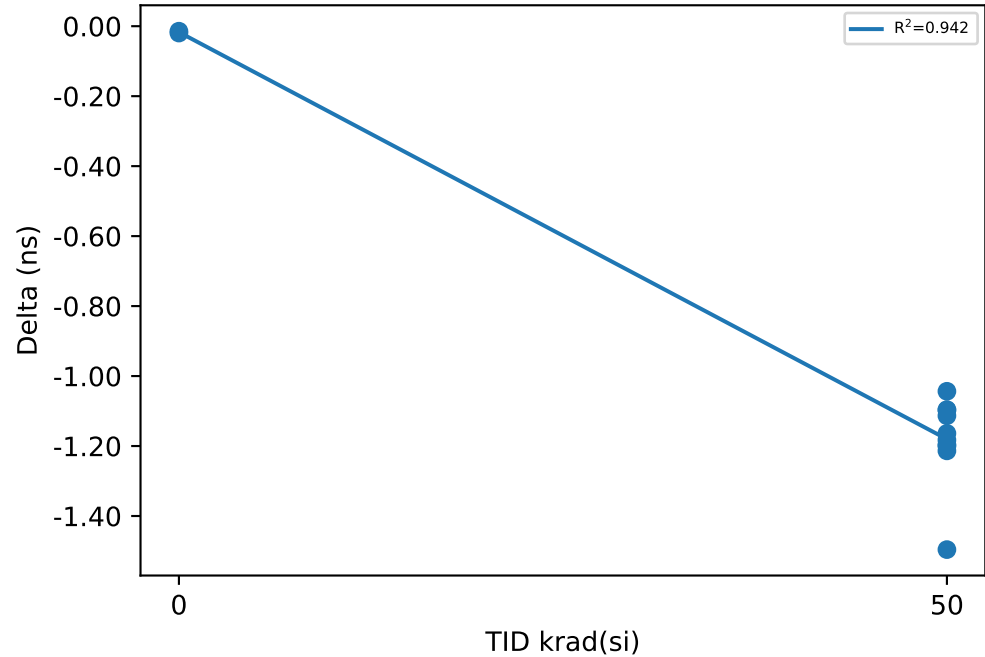
TID vs Result Stats



Test Results (Upper Limit = 65.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	51.539	51.52	-0.0196
2	0	Correlation	51.523	51.509	-0.0143
4	50	Bias	50.769	49.569	-1.1997
6	50	Bias	50.912	49.816	-1.096
7	50	Bias	51.013	49.799	-1.2138
8	50	Bias	50.948	49.851	-1.0973
9	50	Bias	51.181	50.017	-1.1639
11	50	Unbias	51.636	50.523	-1.1134
12	50	Unbias	51.71	50.528	-1.1828
13	50	Unbias	51.386	49.89	-1.496
14	50	Unbias	51.185	49.988	-1.1966
15	50	Unbias	51.37	50.326	-1.0435

TID vs Post - Pre Exposure Delta

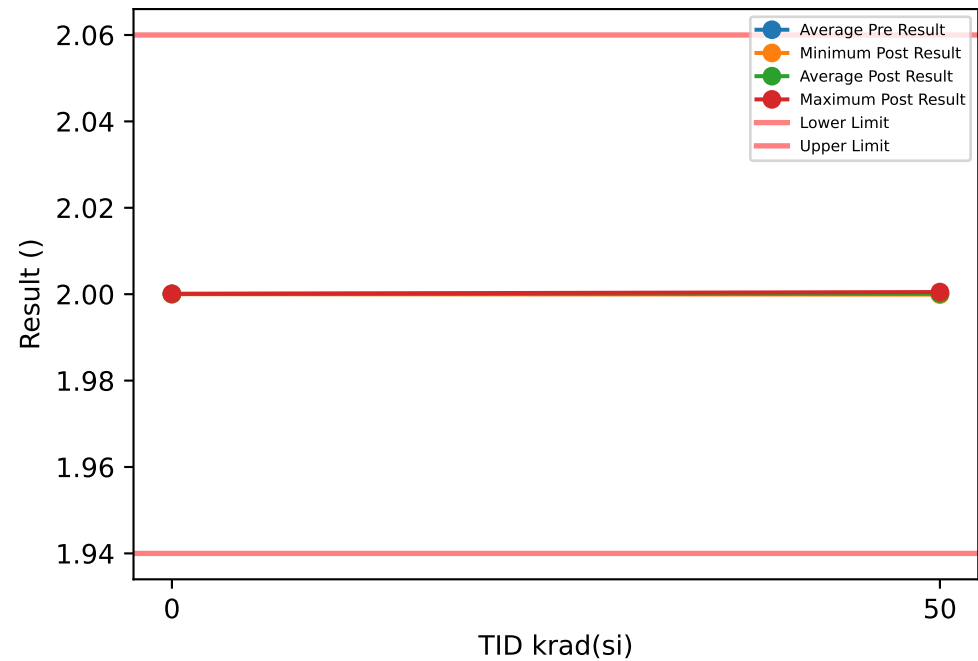


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	51.523	51.531	51.539	0.011172	51.509	51.514	51.52	0.0074246	-0.0196	-0.01695	-0.0143	0.0037477
50	50.769	51.211	51.71	0.31294	49.569	50.031	50.528	0.32381	-1.496	-1.1803	-1.0435	0.12423

Device Test: 28.1 C_CS_R(LEVEL|RATIO/CS/4.5/4.5/0/0/4.5/500kHz//@C_CS_R)

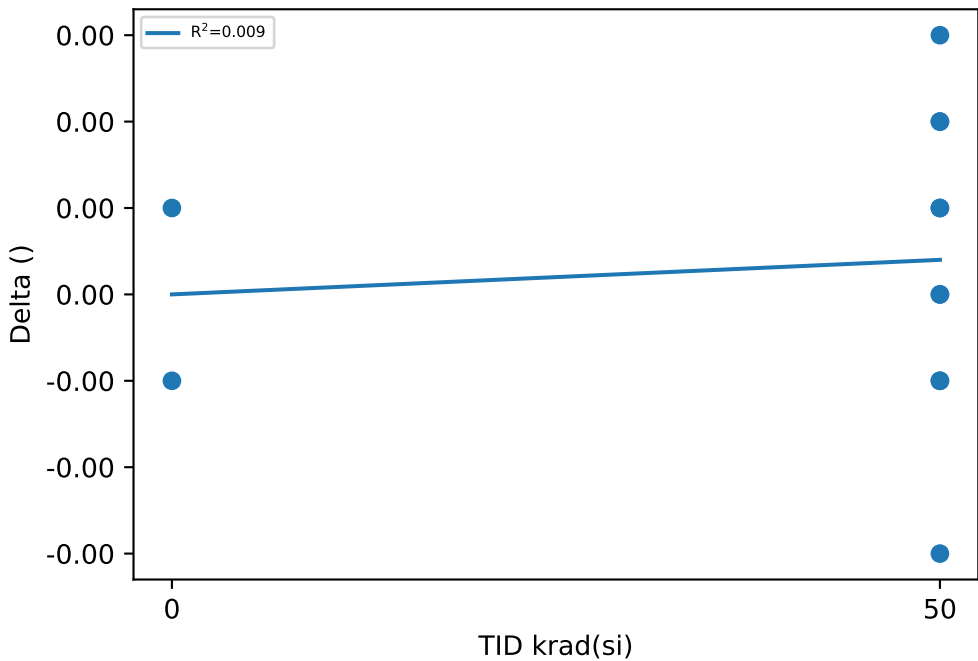
TID vs Result Stats



Test Results (Lower Limit = 1.94, Upper Limit = 2.06 ())

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	2.0001	2	-0.0001
2	0	Correlation	2	2.0001	0.0001
4	50	Bias	1.9999	2.0001	0.0002
6	50	Bias	2	1.9999	-0.0001
7	50	Bias	2	2.0001	0.0001
8	50	Bias	2.0001	2	-0.0001
9	50	Bias	2.0003	2	-0.0003
11	50	Unbias	2	2	0
12	50	Unbias	2.0002	2.0005	0.0003
13	50	Unbias	2.0001	2.0001	0
14	50	Unbias	1.9998	2	0.0002
15	50	Unbias	2.0003	2.0004	0.0001

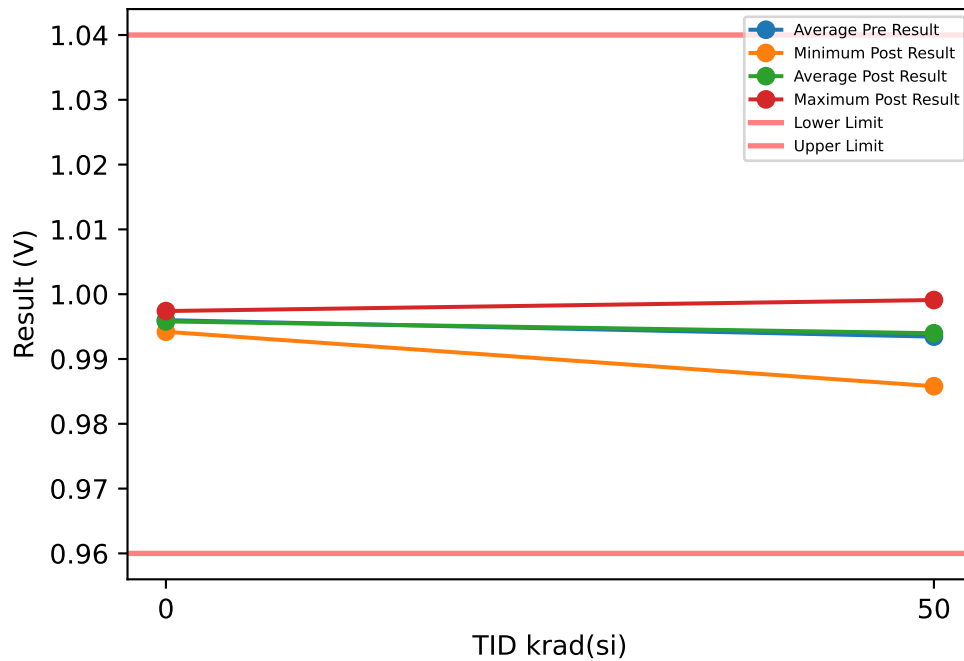
TID vs Post - Pre Exposure Delta



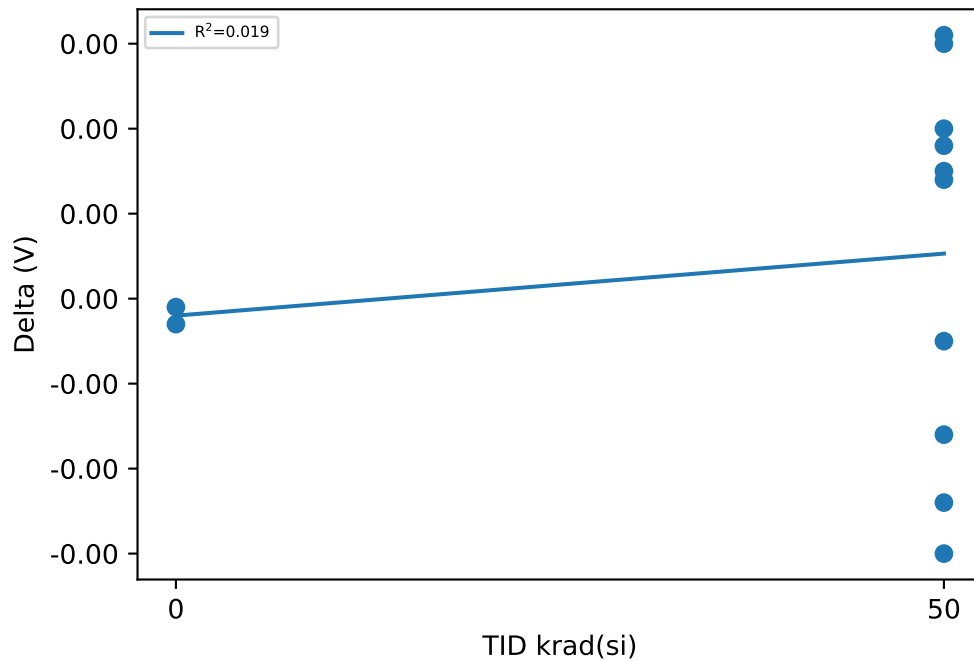
Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2	2	2.0001	7.0711e-05	2	2	2.0001	7.0711e-05	-0.0001	0	0.0001	0.00014142
50	1.9998	2.0001	2.0003	0.00016364	1.9999	2.0001	2.0005	0.0001912	-0.0003	4e-05	0.0003	0.00017764

Device Test: 28.10 V_CS_ILIM_OC(VOLTAGE|OC/CS/5/5/0/0/5/100kHz//@V_CS_ILIM_OC)



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.96,
Upper Limit = 1.04 (V))

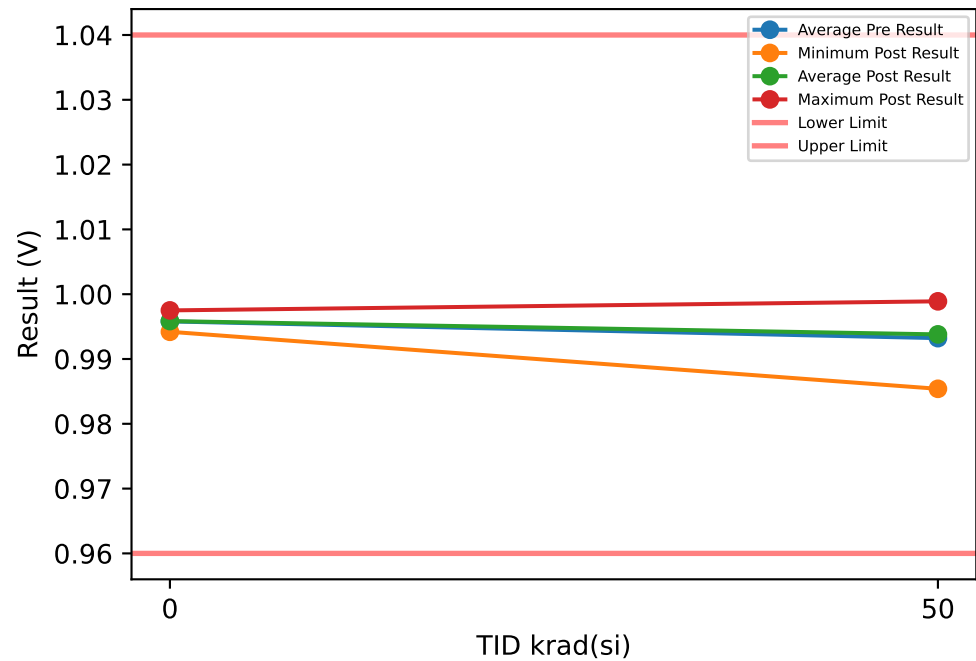
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.9945	0.9942	-0.0003
2	0	Correlation	0.9975	0.9974	-0.0001
4	50	Bias	0.9882	0.9858	-0.0024
6	50	Bias	0.99	0.9914	0.0014
7	50	Bias	0.9943	0.9973	0.003
8	50	Bias	0.9943	0.9974	0.0031
9	50	Bias	0.9955	0.9973	0.0018
11	50	Unbias	0.9913	0.9897	-0.0016
12	50	Unbias	0.9902	0.9917	0.0015
13	50	Unbias	0.9918	0.9913	-0.0005
14	50	Unbias	1.0018	0.9988	-0.003
15	50	Unbias	0.9971	0.9991	0.002

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9945	0.996	0.9975	0.0021213	0.9942	0.9958	0.9974	0.0022627	-0.0003	-0.0002	-0.0001	0.00014142
50	0.9882	0.99345	1.0018	0.0040286	0.9858	0.99398	0.9991	0.0045638	-0.003	0.00053	0.0031	0.0022316

Device Test: 28.11 V_CS_ILIM_OC(VOLTAGE|OC/CS/12/12/0/0/5/100kHz//@V_CS_ILIM_OC)

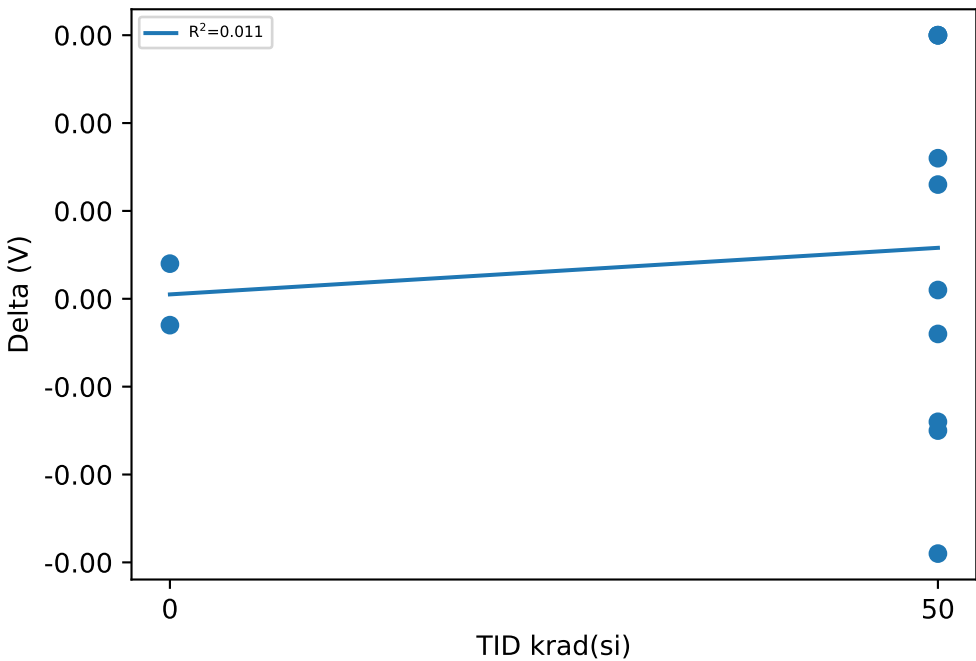
TID vs Result Stats



Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.9945	0.9942	-0.0003
2	0	Correlation	0.9971	0.9975	0.0004
4	50	Bias	0.9883	0.9854	-0.0029
6	50	Bias	0.9883	0.9913	0.003
7	50	Bias	0.9945	0.9975	0.003
8	50	Bias	0.9943	0.9973	0.003
9	50	Bias	0.996	0.9973	0.0013
11	50	Unbias	0.9914	0.9899	-0.0015
12	50	Unbias	0.9902	0.9918	0.0016
13	50	Unbias	0.9914	0.9915	0.0001
14	50	Unbias	1.0003	0.9989	-0.0014
15	50	Unbias	0.9975	0.9971	-0.0004

TID vs Post - Pre Exposure Delta

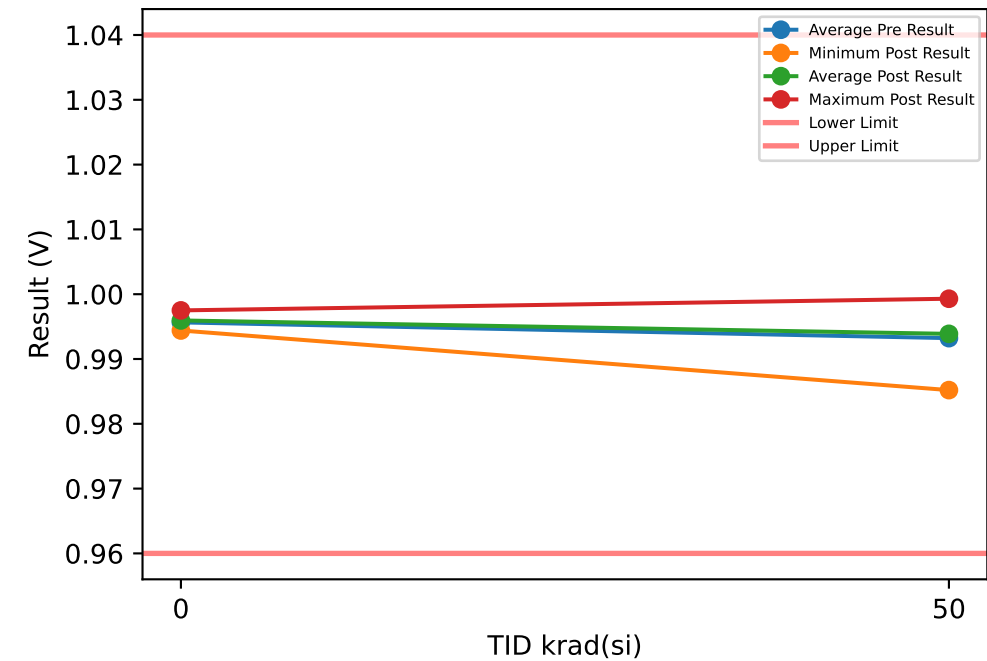


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9945	0.9958	0.9971	0.0018385	0.9942	0.99585	0.9975	0.0023335	-0.0003	5e-05	0.0004	0.00049497
50	0.9883	0.99322	1.0003	0.003988	0.9854	0.9938	0.9989	0.0044272	-0.0029	0.00058	0.003	0.0021259

Device Test: 28.12 V_CS_ILIM_OC(VOLTAGE|OC/CS/14/14/0/0/5/100kHz//@V_CS_ILIM_OC)

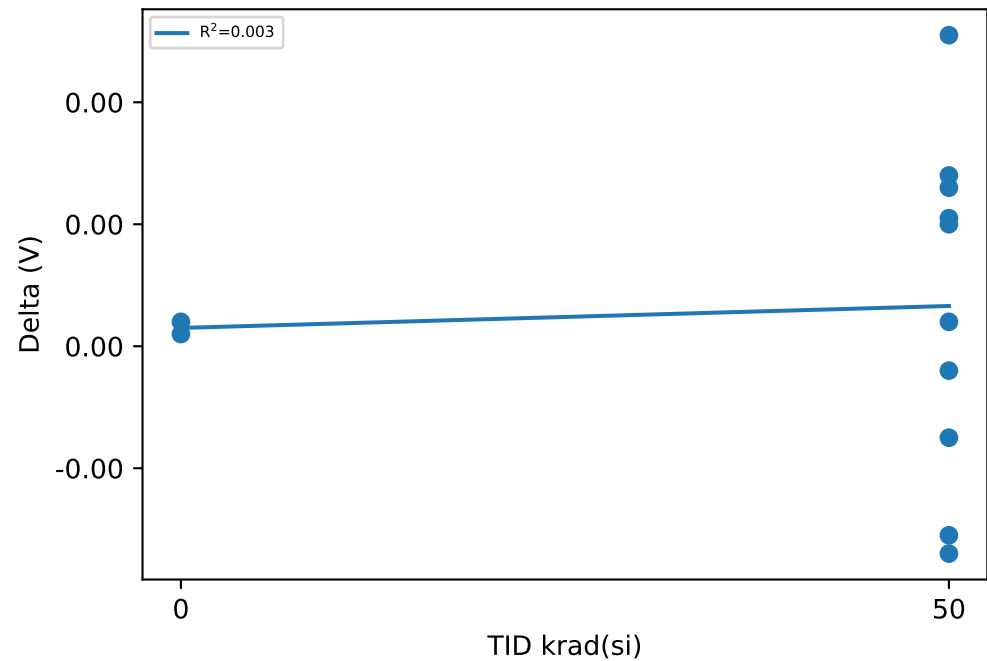
TID vs Result Stats



Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.994	0.9944	0.0004
2	0	Correlation	0.9973	0.9975	0.0002
4	50	Bias	0.9883	0.9852	-0.0031
6	50	Bias	0.9897	0.9918	0.0021
7	50	Bias	0.9945	0.9971	0.0026
8	50	Bias	0.9948	0.9976	0.0028
9	50	Bias	0.9942	0.9993	0.0051
11	50	Unbias	0.9917	0.9883	-0.0034
12	50	Unbias	0.9895	0.9915	0.002
13	50	Unbias	0.9913	0.9917	0.0004
14	50	Unbias	1.0004	0.9989	-0.0015
15	50	Unbias	0.9978	0.9974	-0.0004

TID vs Post - Pre Exposure Delta

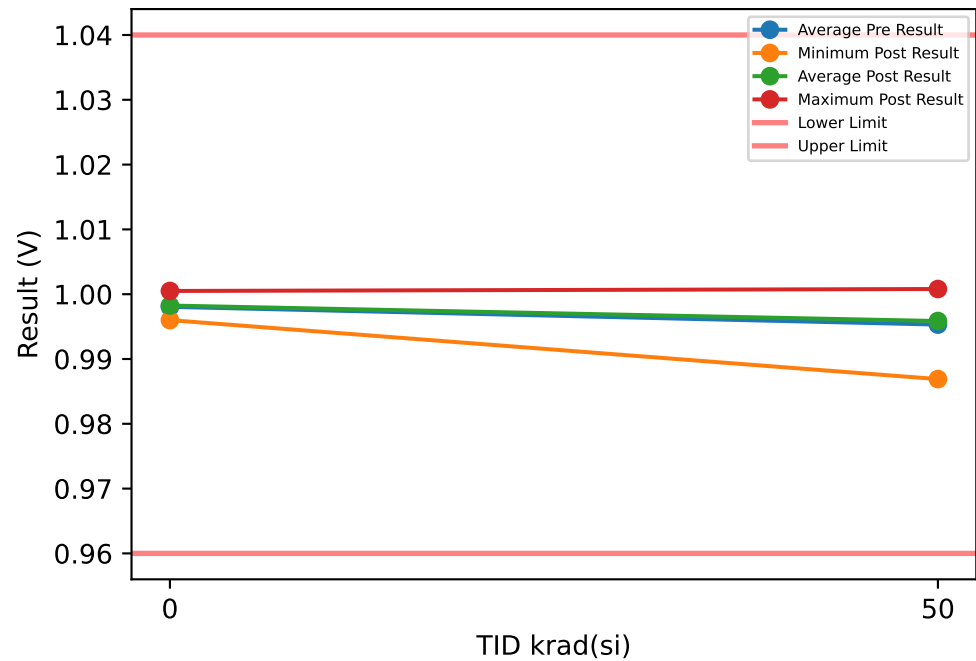


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.994	0.99565	0.9973	0.0023335	0.9944	0.99595	0.9975	0.002192	0.0002	0.0003	0.0004	0.00014142
50	0.9883	0.99322	1.0004	0.0038594	0.9852	0.99388	0.9993	0.0048579	-0.0034	0.00066	0.0051	0.0027569

Device Test: 28.13 V_CS_ILIM_OC(VOLTAGE|OC/CS/4.5/4.5/0/0/4.5/500kHz//@V_CS_ILIM_OC)

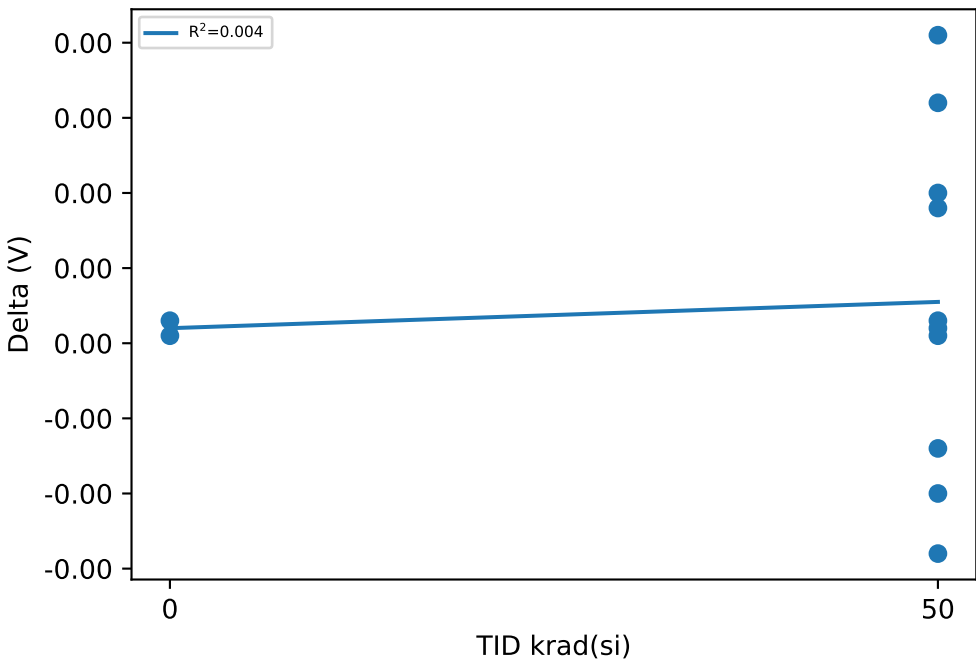
TID vs Result Stats



Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.9957	0.996	0.0003
2	0	Correlation	1.0004	1.0005	0.0001
4	50	Bias	0.9897	0.9869	-0.0028
6	50	Bias	0.9913	0.9933	0.002
7	50	Bias	0.9959	0.9991	0.0032
8	50	Bias	0.996	1.0001	0.0041
9	50	Bias	0.9973	0.9991	0.0018
11	50	Unbias	0.9932	0.9918	-0.0014
12	50	Unbias	0.9927	0.9929	0.0002
13	50	Unbias	0.9944	0.9945	0.0001
14	50	Unbias	1.0021	1.0001	-0.002
15	50	Unbias	1.0005	1.0008	0.0003

TID vs Post - Pre Exposure Delta

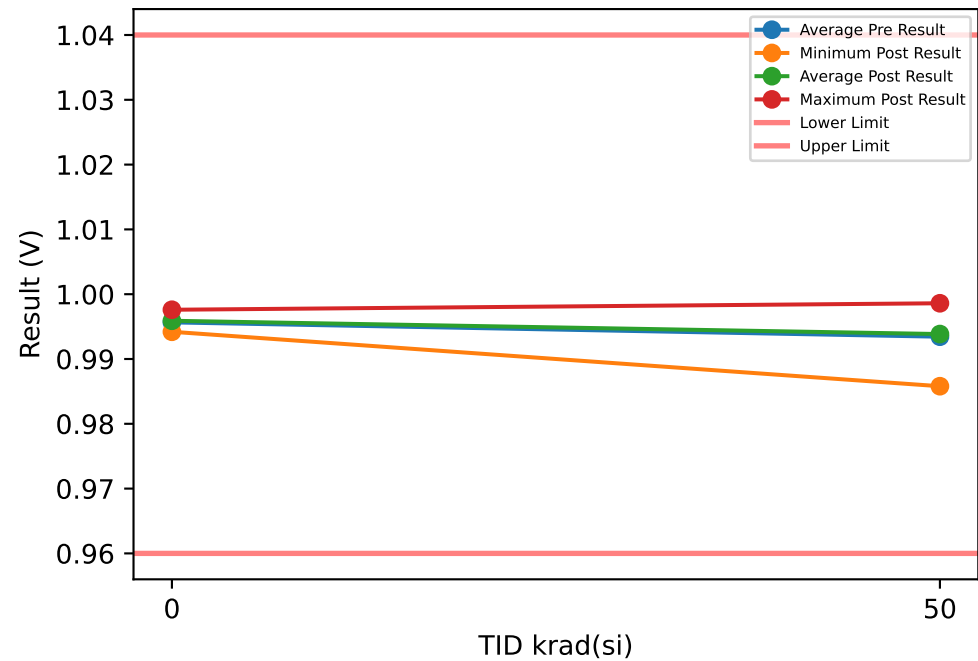


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9957	0.99805	1.0004	0.0033234	0.996	0.99825	1.0005	0.003182	0.0001	0.0002	0.0003	0.00014142
50	0.9897	0.99531	1.0021	0.0039082	0.9869	0.99586	1.0008	0.0046581	-0.0028	0.00055	0.0041	0.0022412

Device Test: 28.14 V_CS_ILIM_OC(VOLTAGE|OC/CS/5/5/0/0/5/500kHz//@V_CS_ILIM_OC)

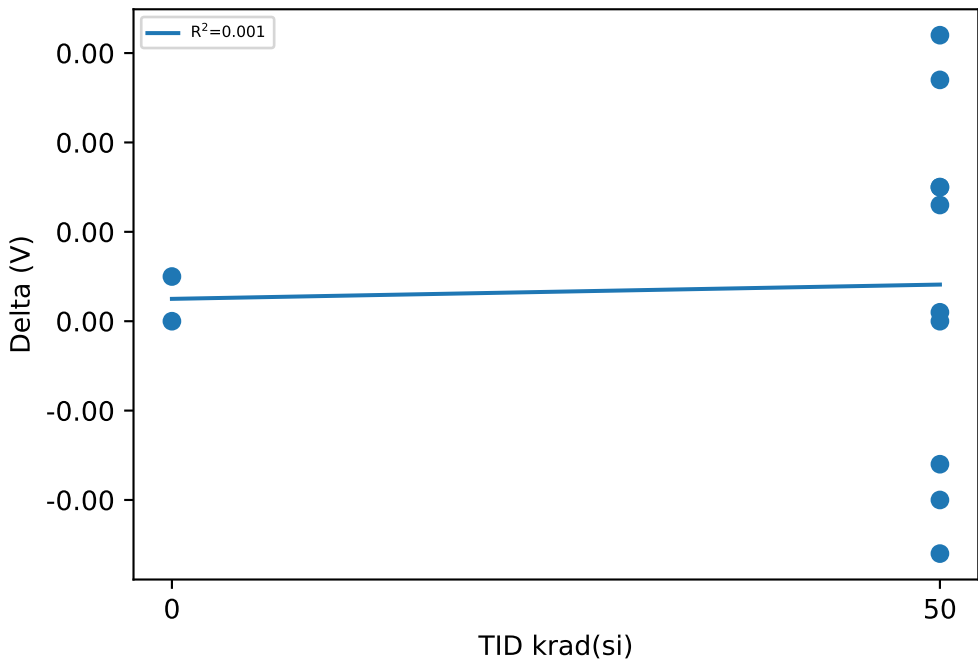
TID vs Result Stats



Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.9942	0.9942	0
2	0	Correlation	0.9971	0.9976	0.0005
4	50	Bias	0.9884	0.9858	-0.0026
6	50	Bias	0.9899	0.9914	0.0015
7	50	Bias	0.9944	0.9971	0.0027
8	50	Bias	0.9944	0.9976	0.0032
9	50	Bias	0.996	0.9973	0.0013
11	50	Unbias	0.9918	0.9902	-0.0016
12	50	Unbias	0.9898	0.9913	0.0015
13	50	Unbias	0.9918	0.9918	0
14	50	Unbias	1.0006	0.9986	-0.002
15	50	Unbias	0.9973	0.9974	0.0001

TID vs Post - Pre Exposure Delta

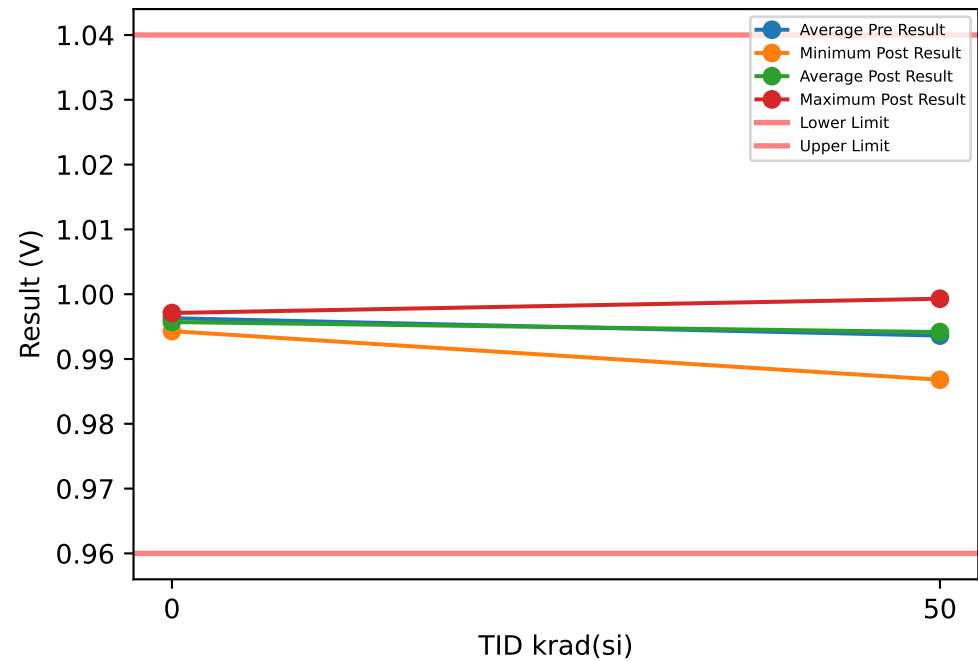


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9942	0.99565	0.9971	0.0020506	0.9942	0.9959	0.9976	0.0024042	0	0.00025	0.0005	0.00035355
50	0.9884	0.99344	1.0006	0.003817	0.9858	0.99385	0.9986	0.0043015	-0.0026	0.00041	0.0032	0.0019824

Device Test: 28.15 V_CS_ILIM_OC(VOLTAGE|OC/CS/12/12/0/0/5/500kHz//@V_CS_ILIM_OC)

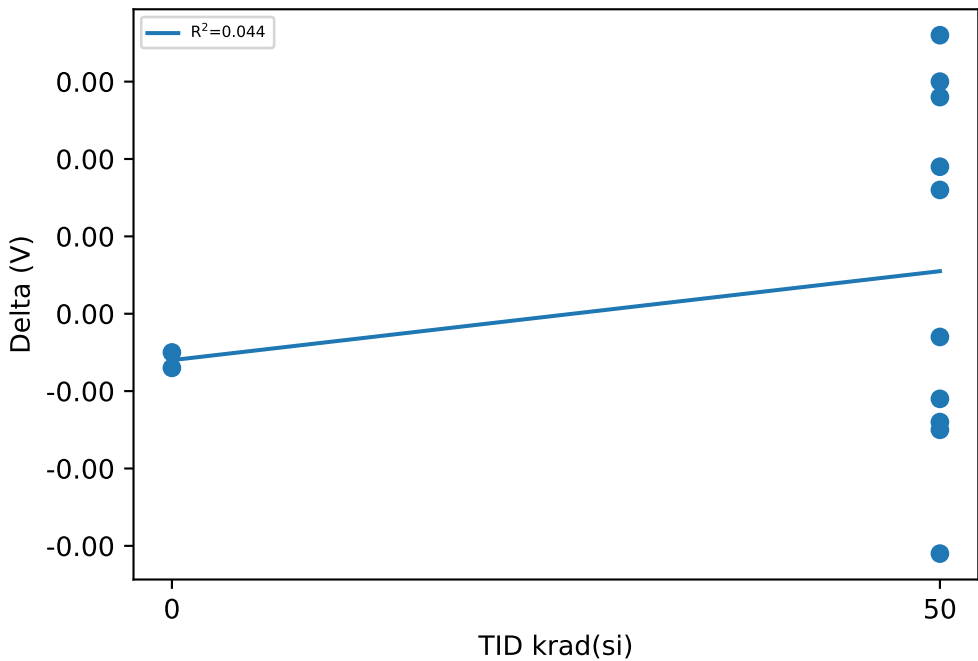
TID vs Result Stats



Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.9948	0.9943	-0.0005
2	0	Correlation	0.9978	0.9971	-0.0007
4	50	Bias	0.9899	0.9868	-0.0031
6	50	Bias	0.9898	0.9917	0.0019
7	50	Bias	0.9945	0.9973	0.0028
8	50	Bias	0.9943	0.9973	0.003
9	50	Bias	0.9957	0.9993	0.0036
11	50	Unbias	0.9912	0.9898	-0.0014
12	50	Unbias	0.9897	0.9913	0.0016
13	50	Unbias	0.9928	0.9917	-0.0011
14	50	Unbias	1.0006	0.9991	-0.0015
15	50	Unbias	0.9976	0.9973	-0.0003

TID vs Post - Pre Exposure Delta

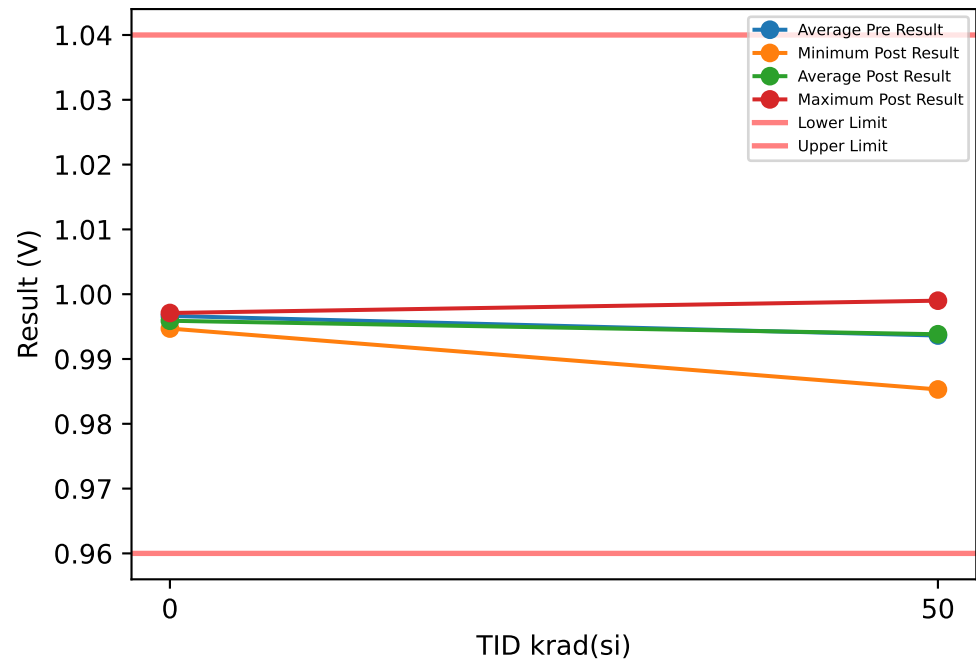


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9948	0.9963	0.9978	0.0021213	0.9943	0.9957	0.9971	0.0019799	-0.0007	-0.0006	-0.0005	0.00014142
50	0.9897	0.99361	1.0006	0.0036583	0.9868	0.99416	0.9993	0.0043952	-0.0031	0.00055	0.0036	0.002311

Device Test: 28.16 V_CS_ILIM_OC(VOLTAGE|OC/CS/14/14/0/0/5/500kHz//@V_CS_ILIM_OC)

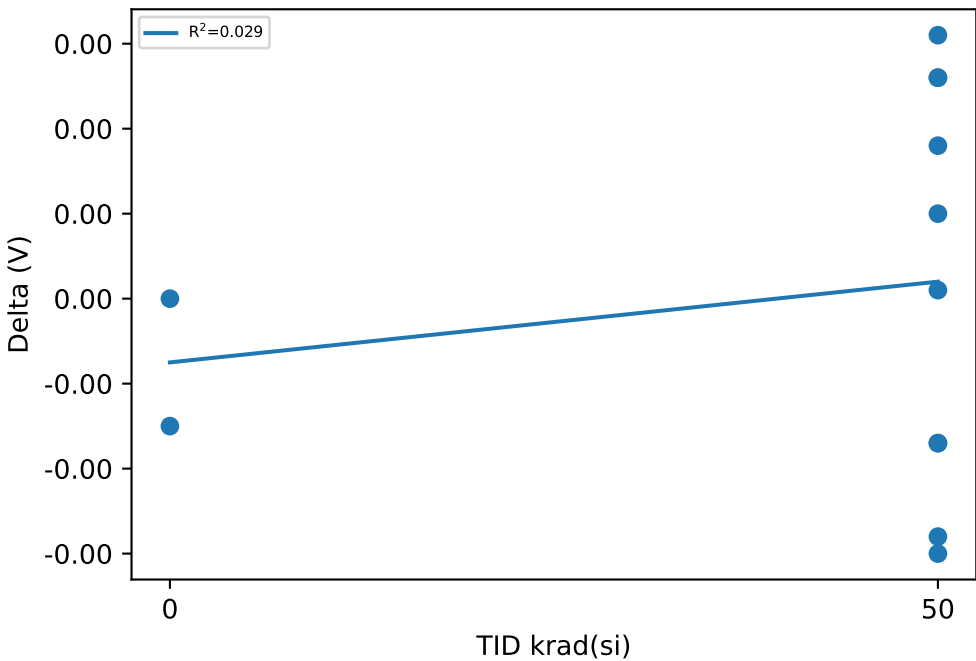
TID vs Result Stats



Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.9947	0.9947	0
2	0	Correlation	0.9986	0.9971	-0.0015
4	50	Bias	0.9883	0.9853	-0.0003
6	50	Bias	0.9895	0.9913	0.0018
7	50	Bias	0.9945	0.9971	0.0026
8	50	Bias	0.9945	0.9971	0.0026
9	50	Bias	0.9957	0.9988	0.0031
11	50	Unbias	0.9914	0.9897	-0.0017
12	50	Unbias	0.9902	0.9912	0.001
13	50	Unbias	0.993	0.9913	-0.0017
14	50	Unbias	1.0018	0.999	-0.0028
15	50	Unbias	0.9973	0.9974	0.0001

TID vs Post - Pre Exposure Delta

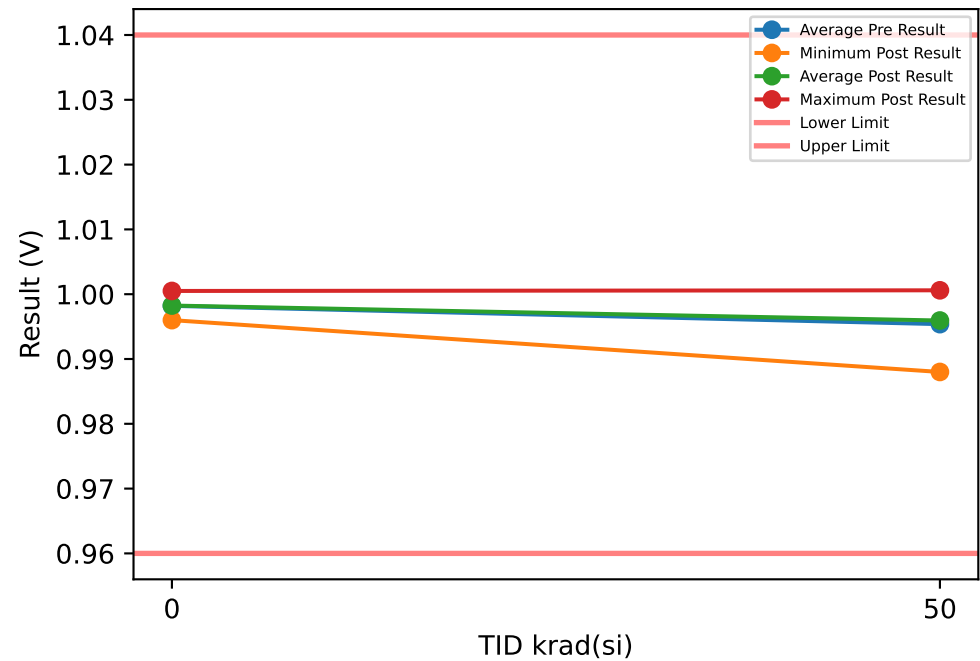


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9947	0.99665	0.9986	0.0027577	0.9947	0.9959	0.9971	0.0016971	-0.0015	-0.00075	0	0.0010607
50	0.9883	0.99362	1.0018	0.0040636	0.9853	0.99382	0.999	0.0046559	-0.0003	0.0002	0.0031	0.0023476

Device Test: 28.17 V_CS_ILIM_OC(VOLTAGE|OC/CS/4.5/4.5/0/0/4.5/1MHz//@V_CS_ILIM_OC)

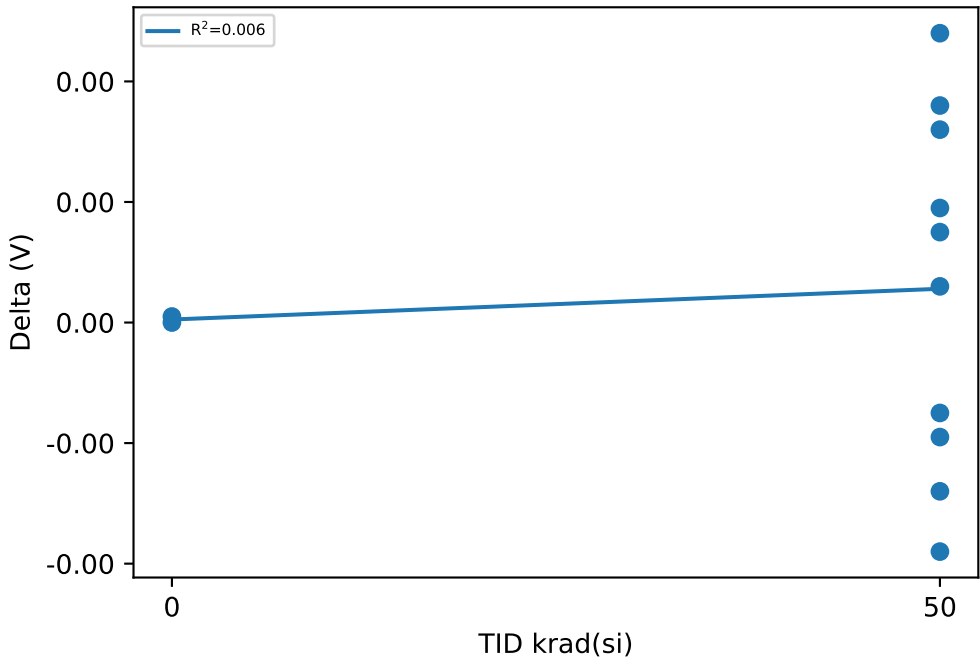
TID vs Result Stats



Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.9959	0.996	0.0001
2	0	Correlation	1.0005	1.0005	0
4	50	Bias	0.9918	0.988	-0.0038
6	50	Bias	0.9915	0.993	0.0015
7	50	Bias	0.9957	0.9993	0.0036
8	50	Bias	0.9958	1.0006	0.0048
9	50	Bias	0.9971	1.0003	0.0032
11	50	Unbias	0.9932	0.9913	-0.0019
12	50	Unbias	0.9927	0.9933	0.0006
13	50	Unbias	0.9943	0.9928	-0.0015
14	50	Unbias	1.0031	1.0003	-0.0028
15	50	Unbias	0.9986	1.0005	0.0019

TID vs Post - Pre Exposure Delta

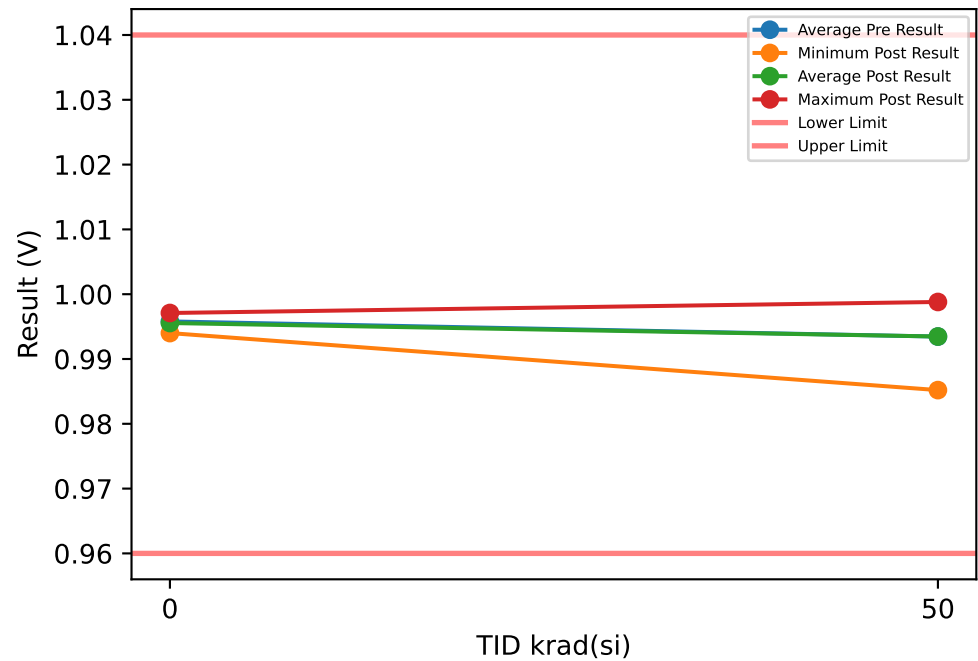


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9959	0.9982	1.0005	0.0032527	0.996	0.99825	1.0005	0.003182	0	5e-05	0.0001	7.0711e-05
50	0.9915	0.99538	1.0031	0.0035618	0.988	0.99594	1.0006	0.004736	-0.0038	0.00056	0.0048	0.0029338

Device Test: 28.18 V_CS_ILIM_OC(VOLTAGE|OC/CS/5/5/0/0/5/1MHz//@V_CS_ILIM_OC)

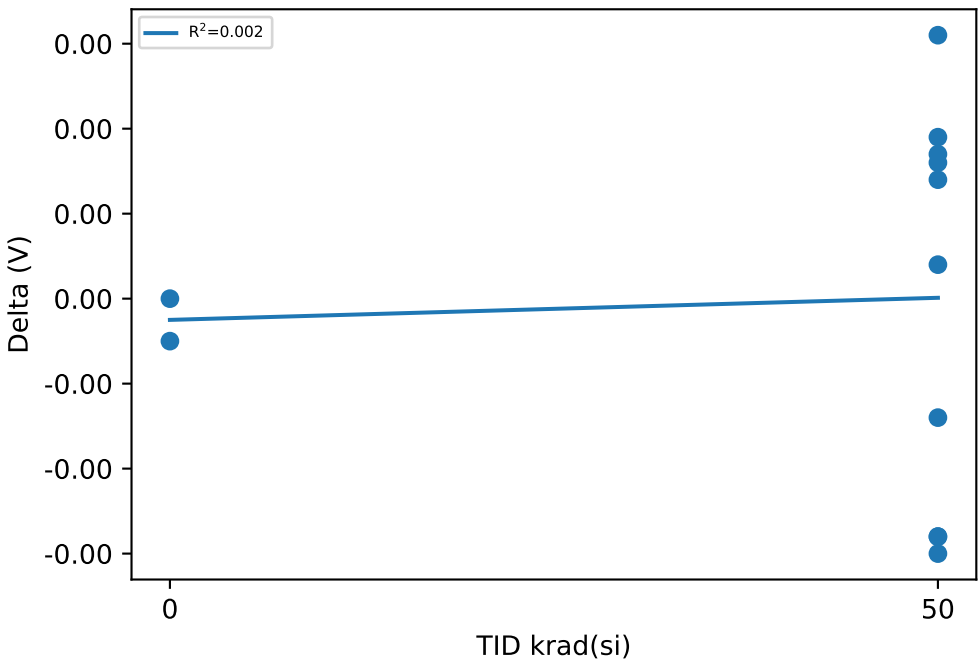
TID vs Result Stats



Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.9945	0.994	-0.0005
2	0	Correlation	0.9971	0.9971	0
4	50	Bias	0.988	0.9852	-0.0028
6	50	Bias	0.9895	0.9914	0.0019
7	50	Bias	0.9942	0.9959	0.0017
8	50	Bias	0.9943	0.9974	0.0031
9	50	Bias	0.9962	0.9976	0.0014
11	50	Unbias	0.9912	0.9882	-0.003
12	50	Unbias	0.9897	0.9913	0.0016
13	50	Unbias	0.9928	0.9914	-0.0014
14	50	Unbias	1.0016	0.9988	-0.0028
15	50	Unbias	0.9971	0.9975	0.0004

TID vs Post - Pre Exposure Delta

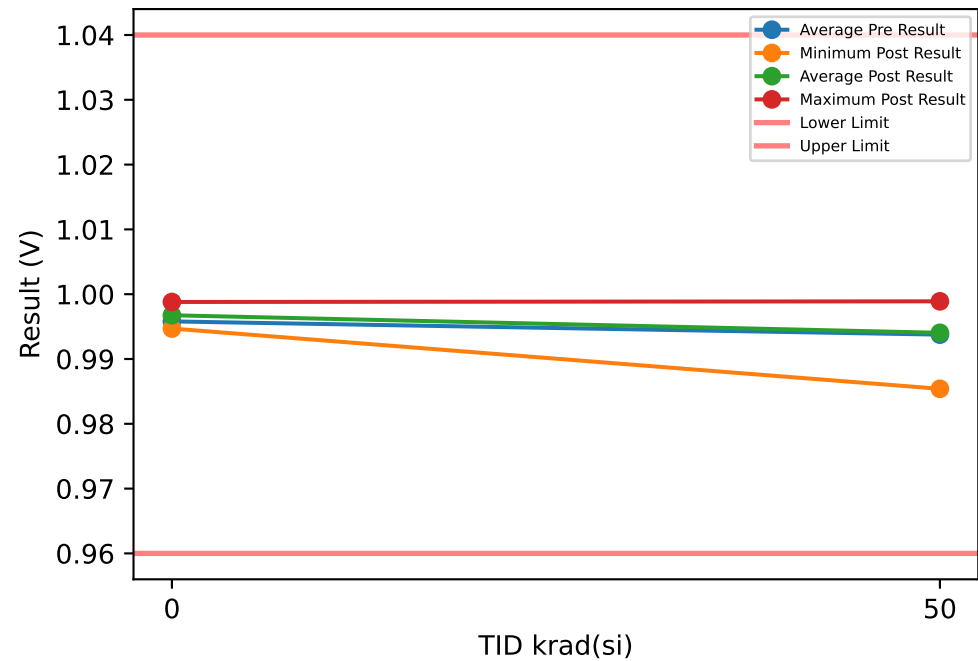


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9945	0.9958	0.9971	0.0018385	0.994	0.99555	0.9971	0.002192	-0.0005	-0.00025	0	0.00035355
50	0.988	0.99346	1.0016	0.0041291	0.9852	0.99347	0.9988	0.0046248	-0.003	1e-05	0.0031	0.0022956

Device Test: 28.19 V_CS_ILIM_OC(VOLTAGE|OC/CS/12/12/0/0/5/1MHz//@V_CS_ILIM_OC)

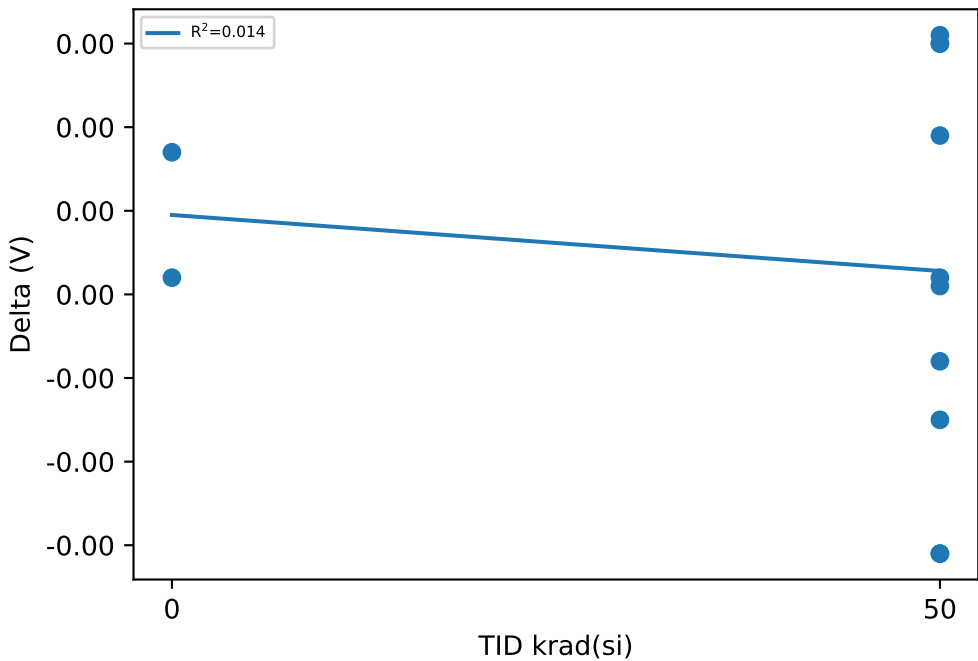
TID vs Result Stats



Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.9945	0.9947	0.0002
2	0	Correlation	0.9971	0.9988	0.0017
4	50	Bias	0.9885	0.9854	-0.0031
6	50	Bias	0.9898	0.9917	0.0019
7	50	Bias	0.9945	0.9976	0.0031
8	50	Bias	0.9945	0.9975	0.003
9	50	Bias	0.9959	0.9989	0.003
11	50	Unbias	0.9912	0.9897	-0.0015
12	50	Unbias	0.9915	0.9917	0.0002
13	50	Unbias	0.9925	0.9917	-0.0008
14	50	Unbias	1.0019	0.9988	-0.0031
15	50	Unbias	0.9973	0.9974	0.0001

TID vs Post - Pre Exposure Delta

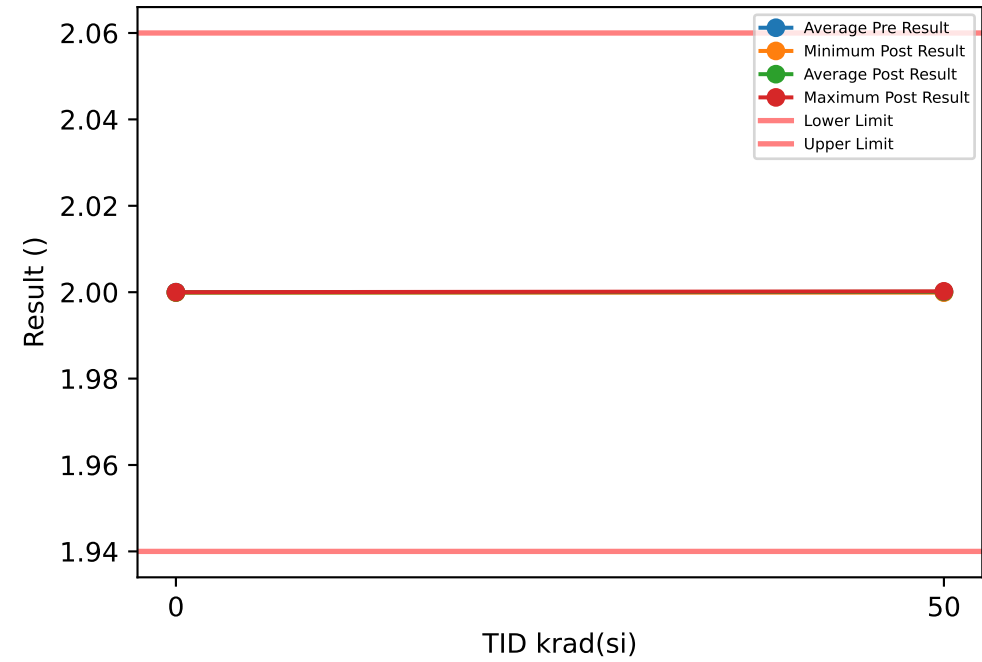


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9945	0.9958	0.9971	0.0018385	0.9947	0.99675	0.9988	0.0028991	0.0002	0.00095	0.0017	0.0010607
50	0.9885	0.99376	1.0019	0.003959	0.9854	0.99404	0.9989	0.0046203	-0.0031	0.00028	0.0031	0.0024174

Device Test: 28.2 C_CS_R(LEVEL|RATIO/CS/5/5/0/0/5/500kHz//@C_CS_R)

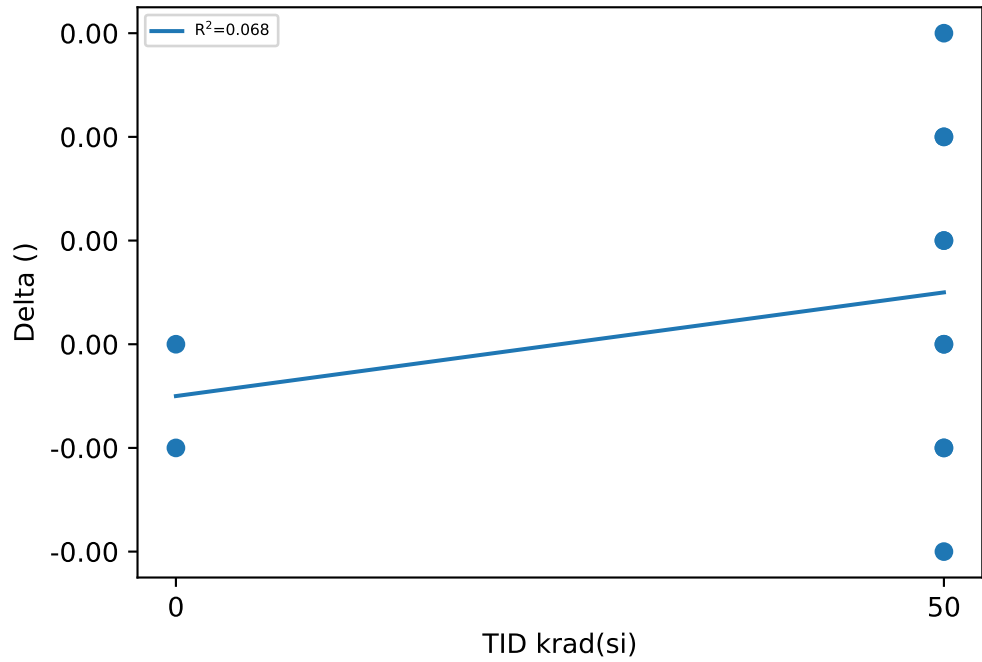
TID vs Result Stats



Test Results (Lower Limit = 1.94, Upper Limit = 2.06 ())

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.9999	1.9999	0
2	0	Correlation	2.0001	2	-0.0001
4	50	Bias	1.9998	2.0001	0.0003
6	50	Bias	2.0001	1.9999	-0.0002
7	50	Bias	2	2.0001	0.0001
8	50	Bias	2.0001	2.0001	0
9	50	Bias	2.0001	2	-0.0001
11	50	Unbias	2.0001	2.0001	0
12	50	Unbias	2	2.0002	0.0002
13	50	Unbias	1.9999	2.0001	0.0002
14	50	Unbias	2	2.0001	0.0001
15	50	Unbias	2.0002	2.0001	-0.0001

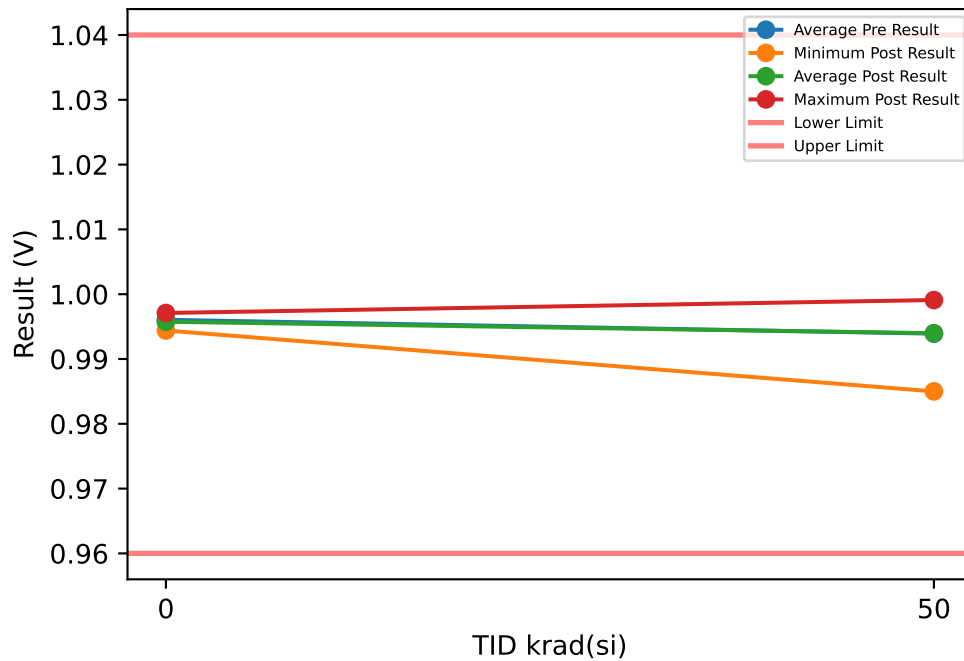
TID vs Post - Pre Exposure Delta



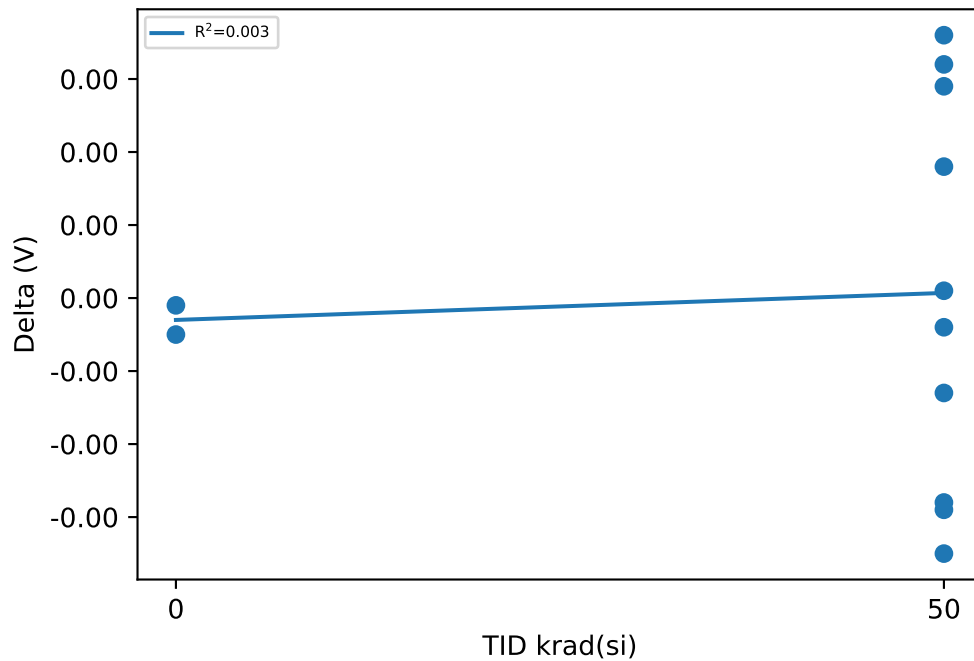
Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9999	2	2.0001	0.00014142	1.9999	2	2	7.0711e-05	-0.0001	-5e-05	0	7.0711e-05
50	1.9998	2	2.0002	0.00011595	1.9999	2.0001	2.0002	7.8881e-05	-0.0002	5e-05	0.0003	0.00015811

Device Test: 28.20 V CS ILIM OC(VOLTAGE|OC/CS/14/14/0/0/5/1MHz//@V CS ILIM OC)



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.96
Upper Limit = 1.04 (V))

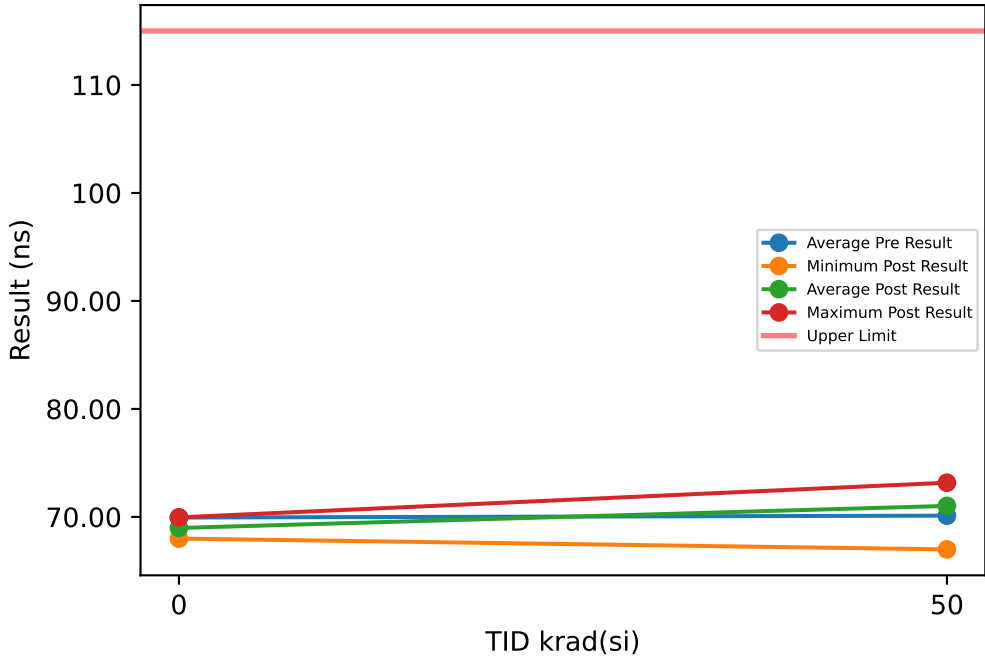
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.9945	0.9944	-0.0001
2	0	Correlation	0.9976	0.9971	-0.0005
4	50	Bias	0.9885	0.985	-0.0035
6	50	Bias	0.9897	0.9915	0.0018
7	50	Bias	0.9944	0.9973	0.0029
8	50	Bias	0.9942	0.9974	0.0032
9	50	Bias	0.9955	0.9991	0.0036
11	50	Unbias	0.993	0.9902	-0.0028
12	50	Unbias	0.9917	0.9913	-0.0004
13	50	Unbias	0.993	0.9917	-0.0013
14	50	Unbias	1.0018	0.9989	-0.0029
15	50	Unbias	0.9973	0.9974	0.0001

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9945	0.99605	0.9976	0.002192	0.9944	0.99575	0.9971	0.0019092	-0.0005	-0.0003	-0.0001	0.00028284
50	0.9885	0.99391	1.0018	0.0038025	0.985	0.99398	0.9991	0.0046939	-0.0035	7e-05	0.0036	0.0026907

Device Test: 28.21 CS_ILIM_DELAY(TIMING|DELAY/CS/4.5/4.5/0/0/4.5/100kHz//@CS_ILIM_DELAY)

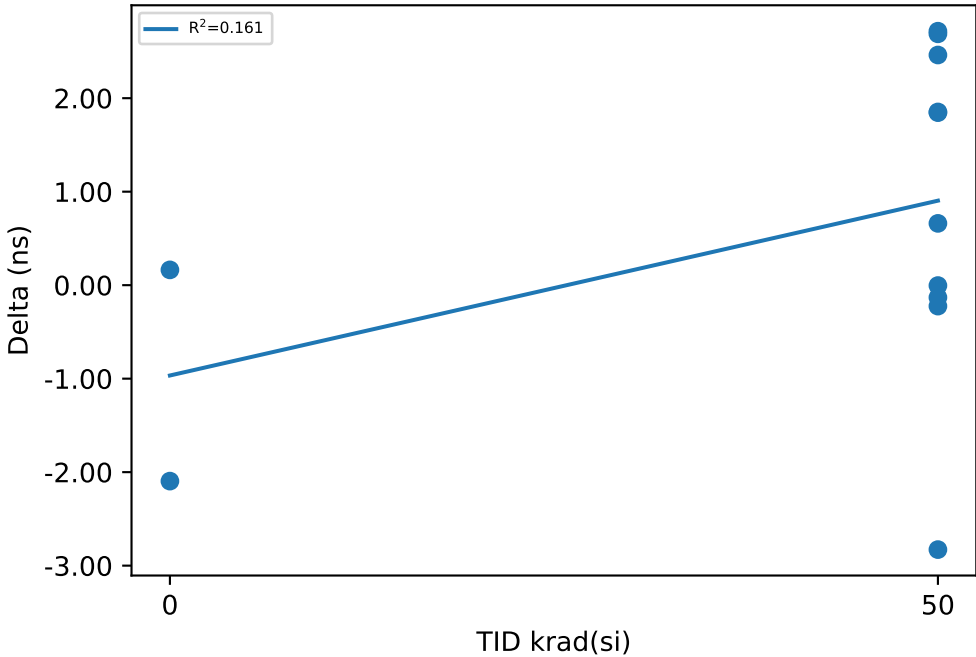
TID vs Result Stats



Test Results (Upper Limit = 115.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	69.794	69.957	0.1635
2	0	Correlation	70.091	67.995	-2.0959
4	50	Bias	69.837	71.69	1.8527
6	50	Bias	69.913	72.375	2.4619
7	50	Bias	70.835	72.681	1.8454
8	50	Bias	70.216	72.933	2.7165
9	50	Bias	70.479	73.167	2.6883
11	50	Unbias	69.58	69.448	-0.1313
12	50	Unbias	69.316	69.976	0.6609
13	50	Unbias	69.82	66.992	-2.8284
14	50	Unbias	71.327	71.323	-0.0041
15	50	Unbias	69.844	69.62	-0.224

TID vs Post - Pre Exposure Delta

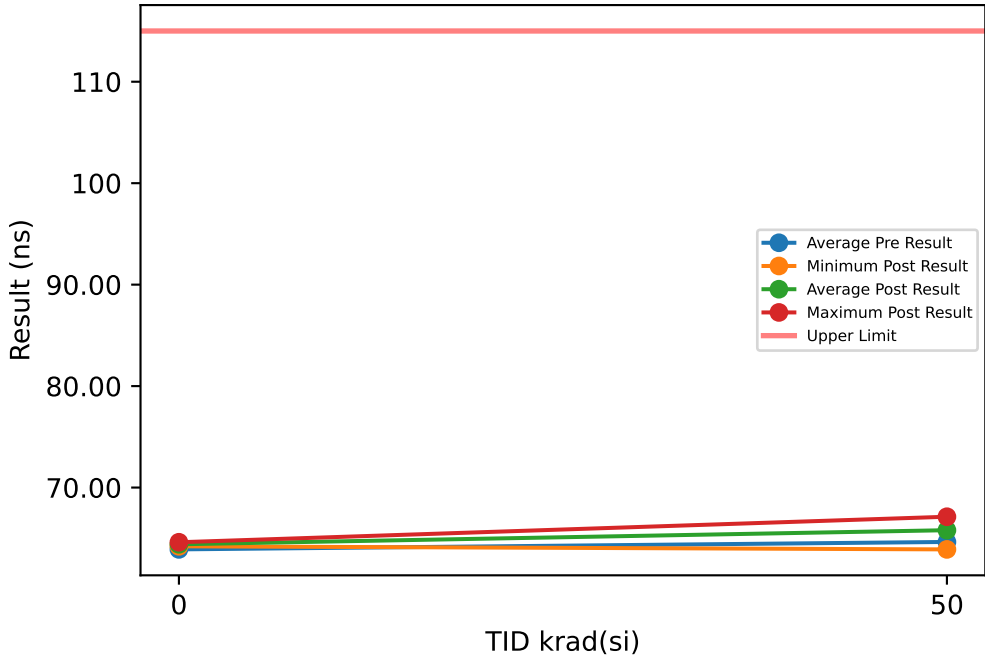


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	69.794	69.942	70.091	0.2098	67.995	68.976	69.957	1.3878	-2.0959	-0.9662	0.1635	1.5976
50	69.316	70.117	71.327	0.6087	66.992	71.021	73.167	1.9762	-2.8284	0.90379	2.7165	1.7588

Device Test: 28.22 CS_ILIM_DELAY(TIMING|DELAY/CS/5/5/0/0/5/100kHz//@CS_ILIM_DELAY)

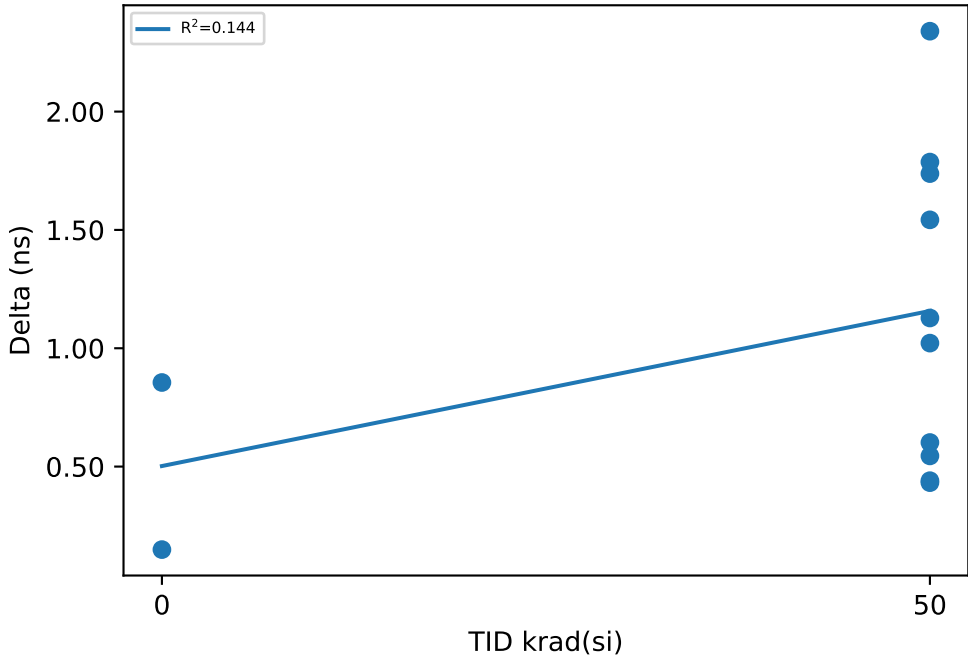
TID vs Result Stats



Test Results (Upper Limit = 115.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	63.753	64.608	0.8553
2	0	Correlation	64.06	64.209	0.1492
4	50	Bias	64.325	66.063	1.738
6	50	Bias	65.137	66.68	1.5426
7	50	Bias	65.265	67.051	1.7867
8	50	Bias	64.784	67.123	2.3397
9	50	Bias	65.624	66.752	1.1279
11	50	Unbias	63.473	63.905	0.4321
12	50	Unbias	63.971	64.573	0.6017
13	50	Unbias	63.744	64.766	1.0217
14	50	Unbias	65.757	66.302	0.5451
15	50	Unbias	64.311	64.751	0.4404

TID vs Post - Pre Exposure Delta

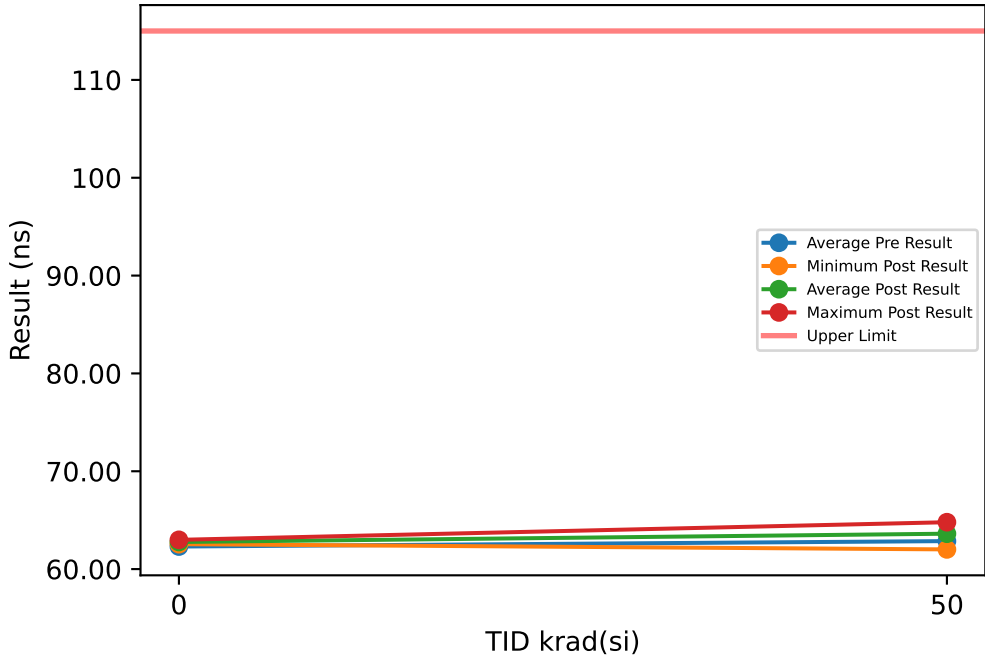


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	63.753	63.906	64.06	0.2168	64.209	64.409	64.608	0.28249	0.1492	0.50225	0.8553	0.49929
50	63.473	64.639	65.757	0.79548	63.905	65.797	67.123	1.1826	0.4321	1.1576	2.3397	0.66854

Device Test: 28.23 CS_ILIM_DELAY(TIMING|DELAY/CS/12/12/0/0/5/100kHz//@CS_ILIM_DELAY)

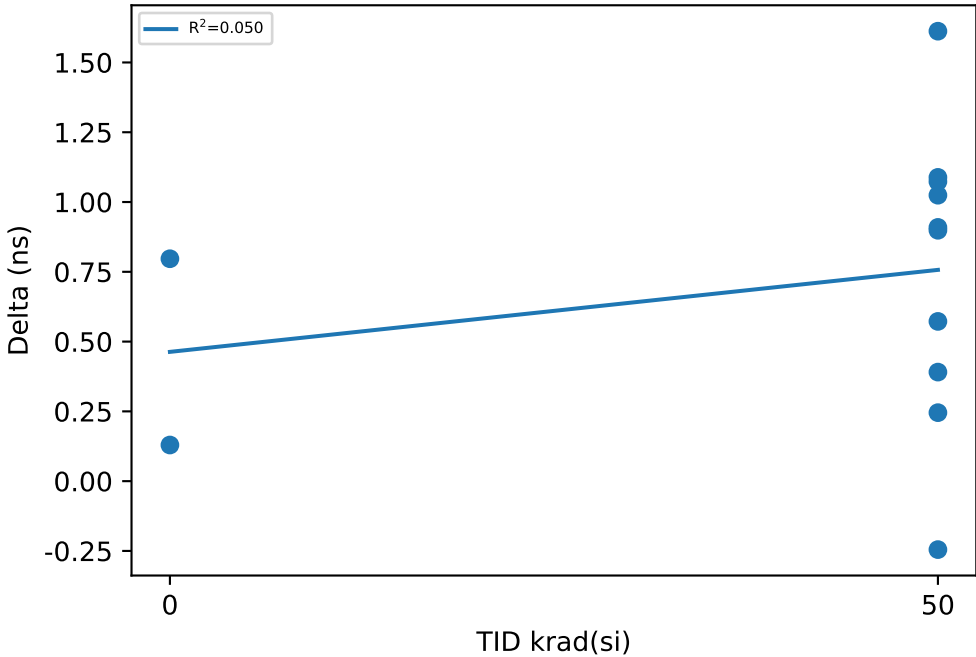
TID vs Result Stats



Test Results (Upper Limit = 115.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	62.193	62.99	0.7968
2	0	Correlation	62.418	62.547	0.1295
4	50	Bias	63.201	64.1	0.8988
6	50	Bias	62.437	63.51	1.0733
7	50	Bias	63.115	64.203	1.0883
8	50	Bias	63.096	64.708	1.612
9	50	Bias	63.767	64.791	1.0244
11	50	Unbias	61.622	62.013	0.3907
12	50	Unbias	62.306	62.879	0.5723
13	50	Unbias	62.262	63.171	0.9091
14	50	Unbias	64.273	64.518	0.2454
15	50	Unbias	62.523	62.278	-0.2452

TID vs Post - Pre Exposure Delta

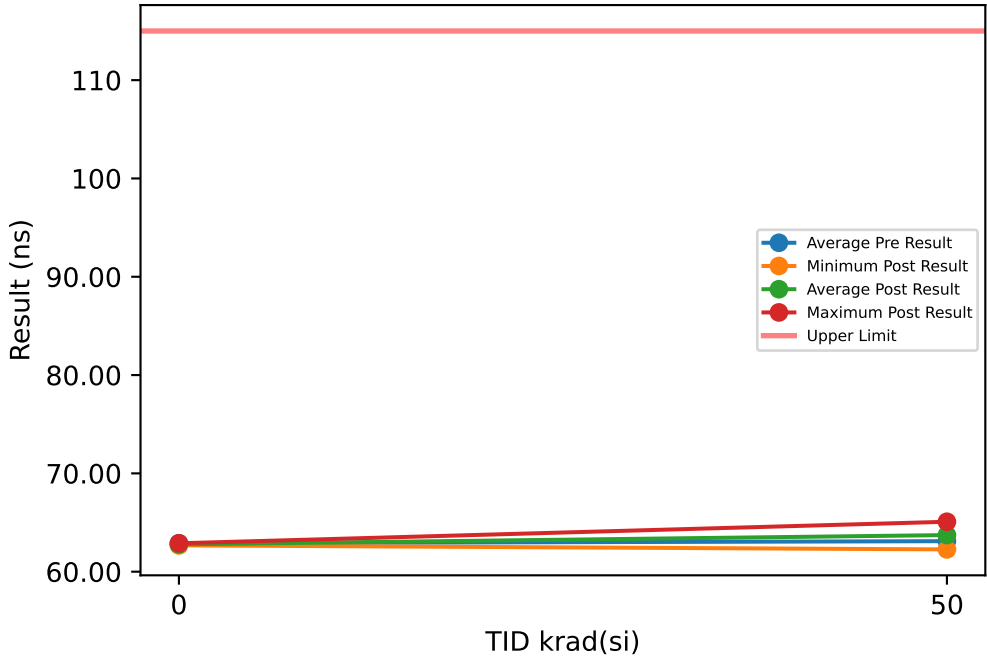


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	62.193	62.306	62.418	0.15896	62.547	62.769	62.99	0.31289	0.1295	0.46315	0.7968	0.47185
50	61.622	62.86	64.273	0.78484	62.013	63.617	64.791	1.0044	-0.2452	0.75691	1.612	0.52599

Device Test: 28.24 CS_ILIM_DELAY(TIMING|DELAY/CS/14/14/0/0/5/100kHz//@CS_ILIM_DELAY)

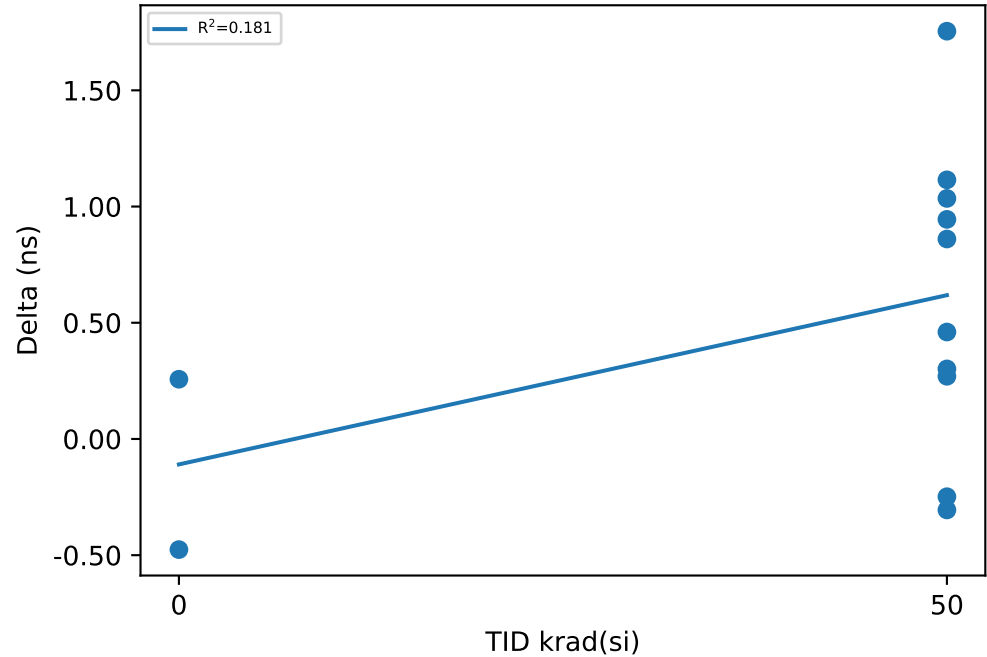
TID vs Result Stats



Test Results (Upper Limit = 115.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	63.152	62.676	-0.476
2	0	Correlation	62.631	62.888	0.257
4	50	Bias	63.384	64.419	1.0349
6	50	Bias	63.301	63.57	0.2697
7	50	Bias	63.504	63.199	-0.3054
8	50	Bias	63.405	64.52	1.1149
9	50	Bias	63.325	65.079	1.7544
11	50	Unbias	61.966	62.267	0.3014
12	50	Unbias	62.252	63.113	0.8603
13	50	Unbias	62.458	63.403	0.9448
14	50	Unbias	64.584	65.044	0.4601
15	50	Unbias	62.864	62.615	-0.2485

TID vs Post - Pre Exposure Delta

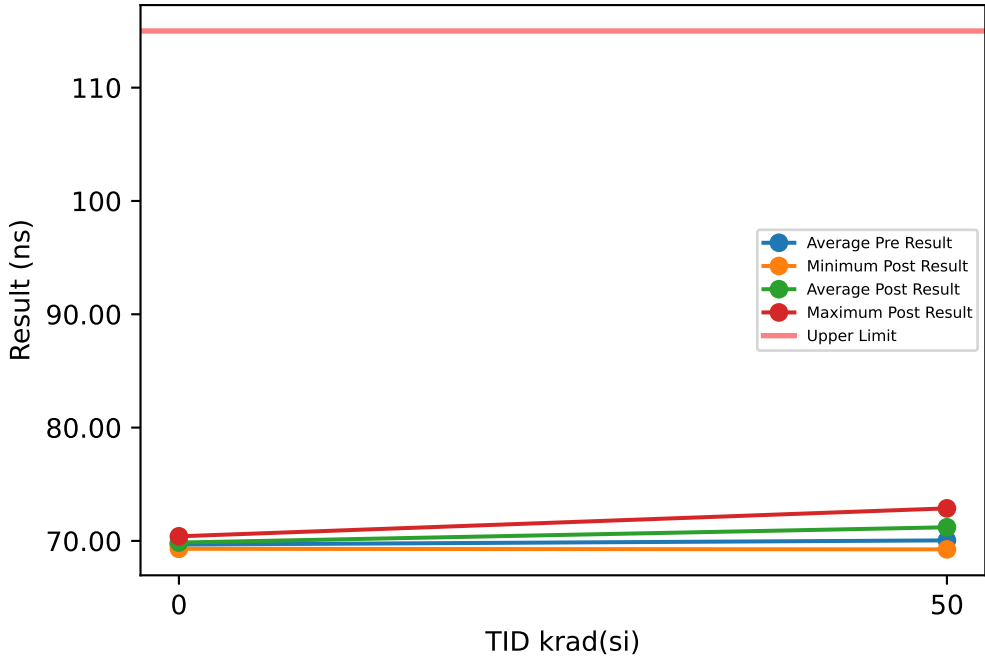


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	62.631	62.892	63.152	0.36847	62.676	62.782	62.888	0.14984	-0.476	-0.1095	0.257	0.51831
50	61.966	63.104	64.584	0.75299	62.267	63.723	65.079	0.99014	-0.3054	0.61866	1.7544	0.64357

Device Test: 28.25 CS_ILIM_DELAY(TIMING|DELAY/CS/4.5/4.5/0/0/4.5/500kHz//@CS_ILIM_DELAY)

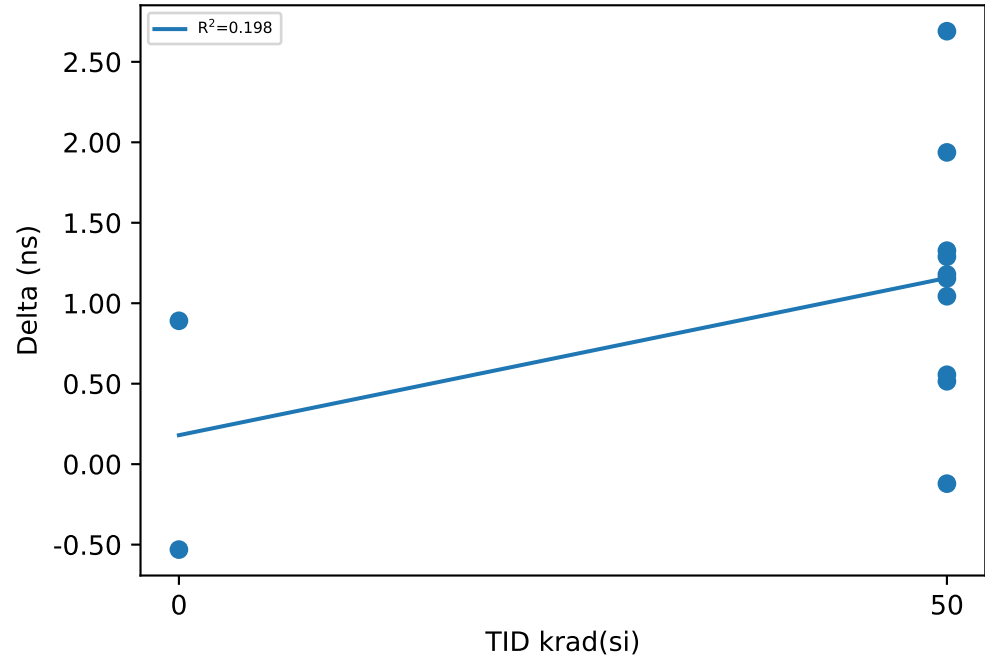
TID vs Result Stats



Test Results (Upper Limit = 115.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	69.835	69.304	-0.5309
2	0	Correlation	69.514	70.405	0.8908
4	50	Bias	70.77	71.813	1.0434
6	50	Bias	70.575	71.754	1.179
7	50	Bias	70.761	72.698	1.9373
8	50	Bias	70.182	72.872	2.6904
9	50	Bias	71.226	72.381	1.1543
11	50	Unbias	68.775	69.29	0.515
12	50	Unbias	69.372	69.251	-0.1211
13	50	Unbias	69.178	70.467	1.2894
14	50	Unbias	70.609	71.165	0.5556
15	50	Unbias	69.018	70.345	1.3267

TID vs Post - Pre Exposure Delta

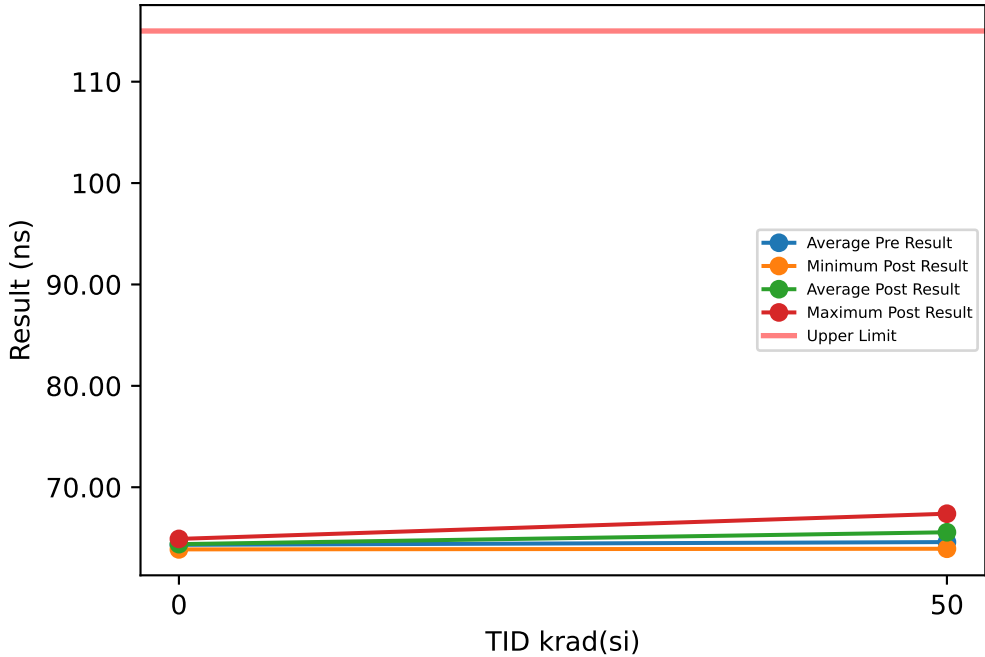


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	69.514	69.674	69.835	0.22677	69.304	69.854	70.405	0.77852	-0.5309	0.17995	0.8908	1.0053
50	68.775	70.047	71.226	0.87721	69.251	71.204	72.872	1.3265	-0.1211	1.157	2.6904	0.77655

Device Test: 28.26 CS_ILIM_DELAY(TIMING|DELAY/CS/5/5/0/0/5/500kHz//@CS_ILIM_DELAY)

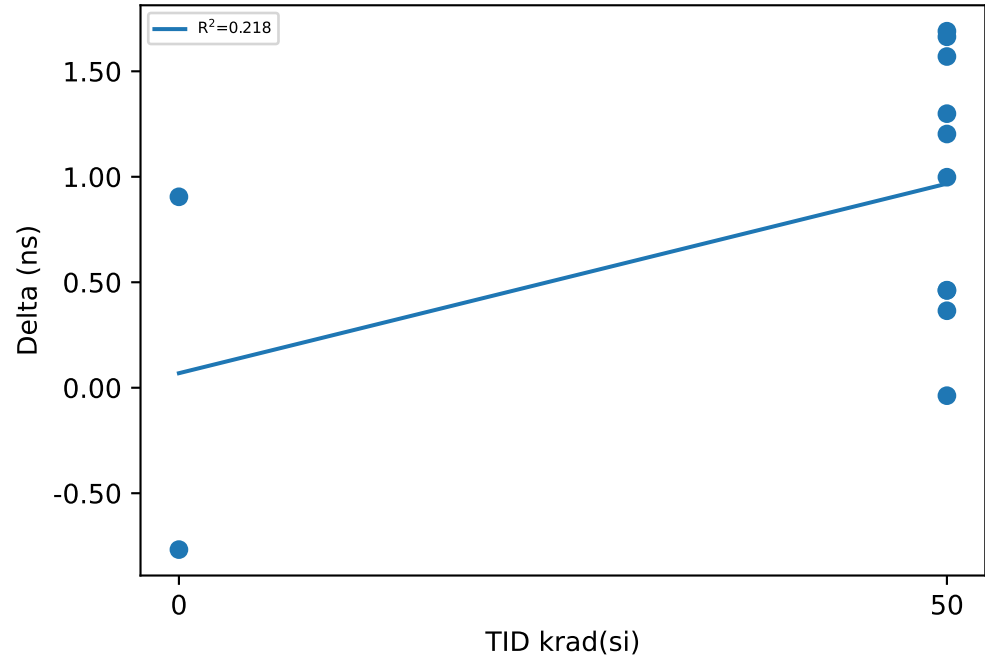
TID vs Result Stats



Test Results (Upper Limit = 115.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	64.636	63.869	-0.7672
2	0	Correlation	63.998	64.903	0.9051
4	50	Bias	64.246	65.909	1.6636
6	50	Bias	65.138	66.136	0.998
7	50	Bias	65.359	67.049	1.6901
8	50	Bias	65.327	66.626	1.2992
9	50	Bias	65.818	67.388	1.5701
11	50	Unbias	63.579	63.944	0.365
12	50	Unbias	63.97	63.932	-0.0376
13	50	Unbias	63.77	64.231	0.4611
14	50	Unbias	65.084	65.546	0.4625
15	50	Unbias	63.616	64.819	1.2028

TID vs Post - Pre Exposure Delta

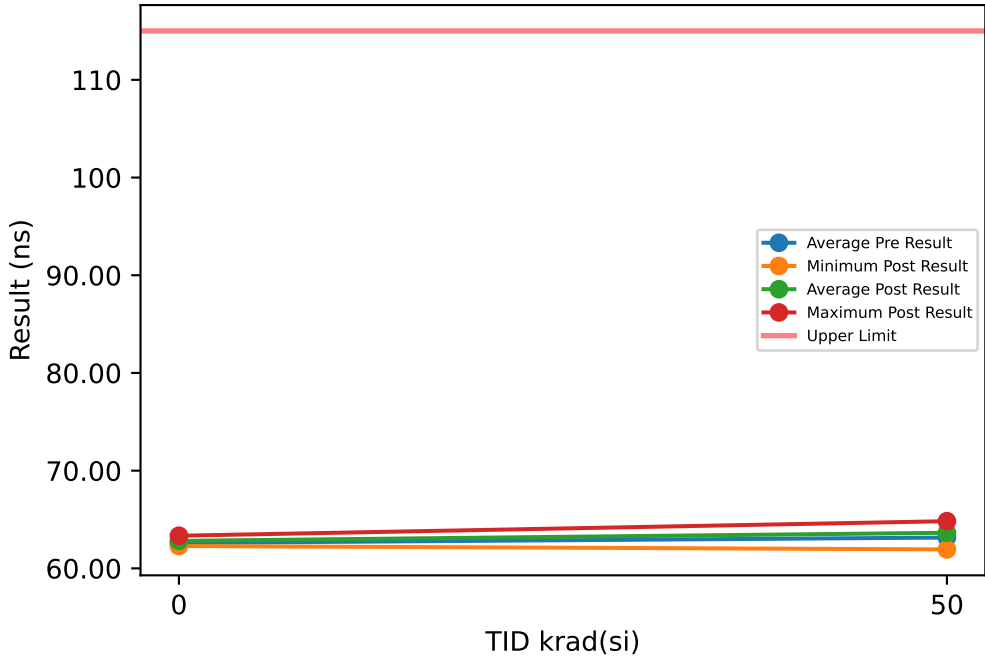


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	63.998	64.317	64.636	0.45085	63.869	64.386	64.903	0.73164	-0.7672	0.06895	0.9051	1.1825
50	63.579	64.591	65.818	0.83878	63.932	65.558	67.388	1.2791	-0.0376	0.96748	1.6901	0.61652

Device Test: 28.27 CS_ILIM_DELAY(TIMING|DELAY/CS/12/12/0/0/5/500kHz//@CS_ILIM_DELAY)

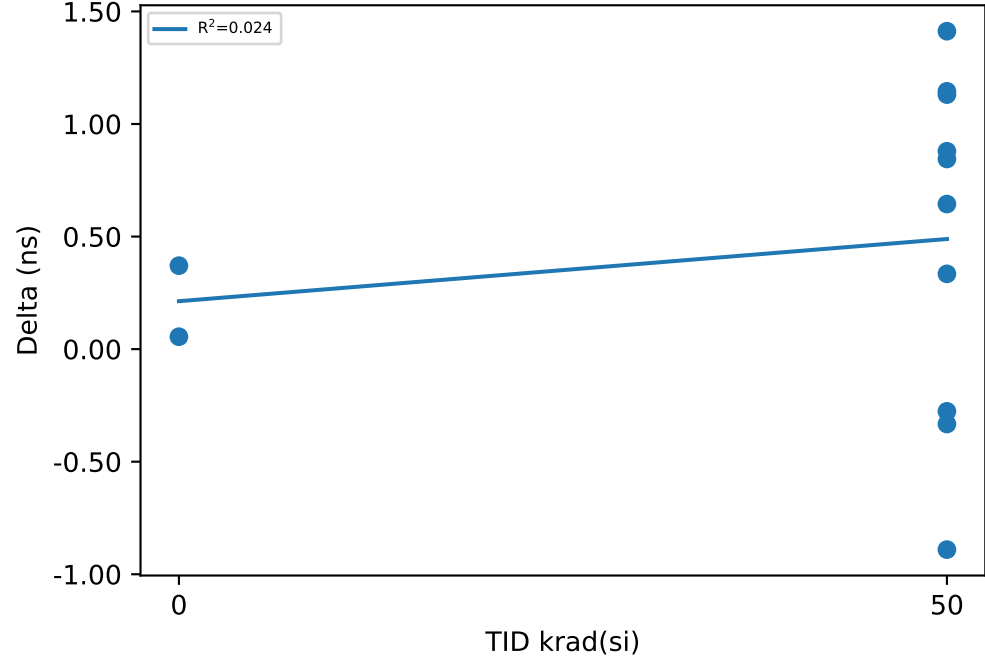
TID vs Result Stats



Test Results (Upper Limit = 115.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	62.233	62.288	0.0551
2	0	Correlation	62.969	63.34	0.3707
4	50	Bias	63.212	64.091	0.879
6	50	Bias	63.026	63.871	0.8446
7	50	Bias	63.62	64.765	1.1452
8	50	Bias	63.699	64.829	1.1306
9	50	Bias	63.289	64.701	1.4122
11	50	Unbias	62.218	61.941	-0.2764
12	50	Unbias	62.324	62.968	0.6444
13	50	Unbias	62.816	62.483	-0.3326
14	50	Unbias	64.296	64.63	0.3343
15	50	Unbias	63.03	62.139	-0.8905

TID vs Post - Pre Exposure Delta

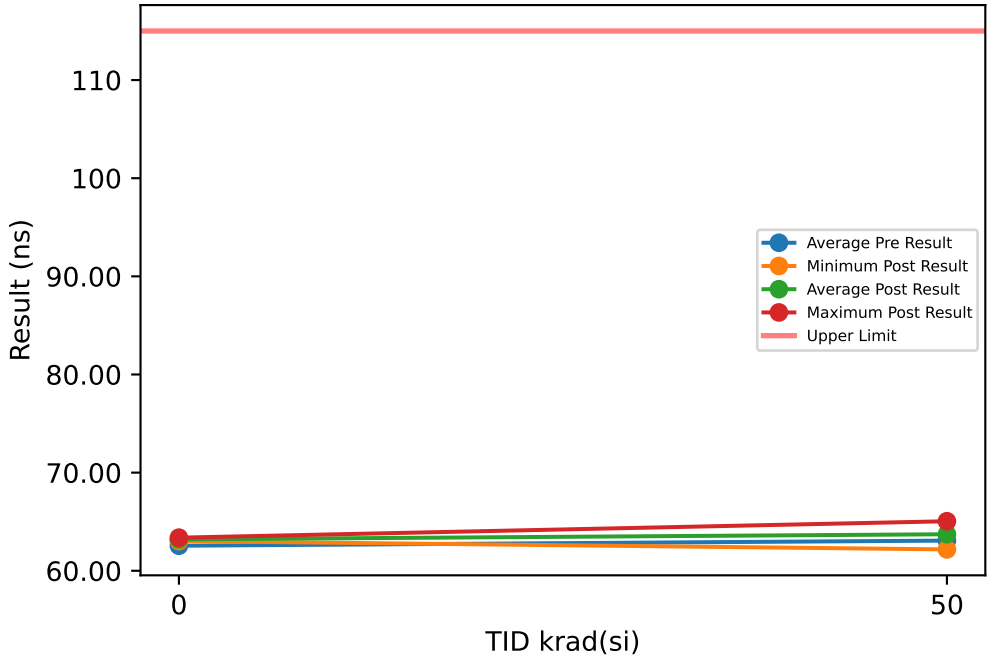


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	62.233	62.601	62.969	0.52064	62.288	62.814	63.34	0.74381	0.0551	0.2129	0.3707	0.22316
50	62.218	63.153	64.296	0.62815	61.941	63.642	64.829	1.1533	-0.8905	0.48908	1.4122	0.75902

Device Test: 28.28 CS_ILIM_DELAY(TIMING|DELAY/CS/14/14/0/0/5/500kHz//@CS_ILIM_DELAY)

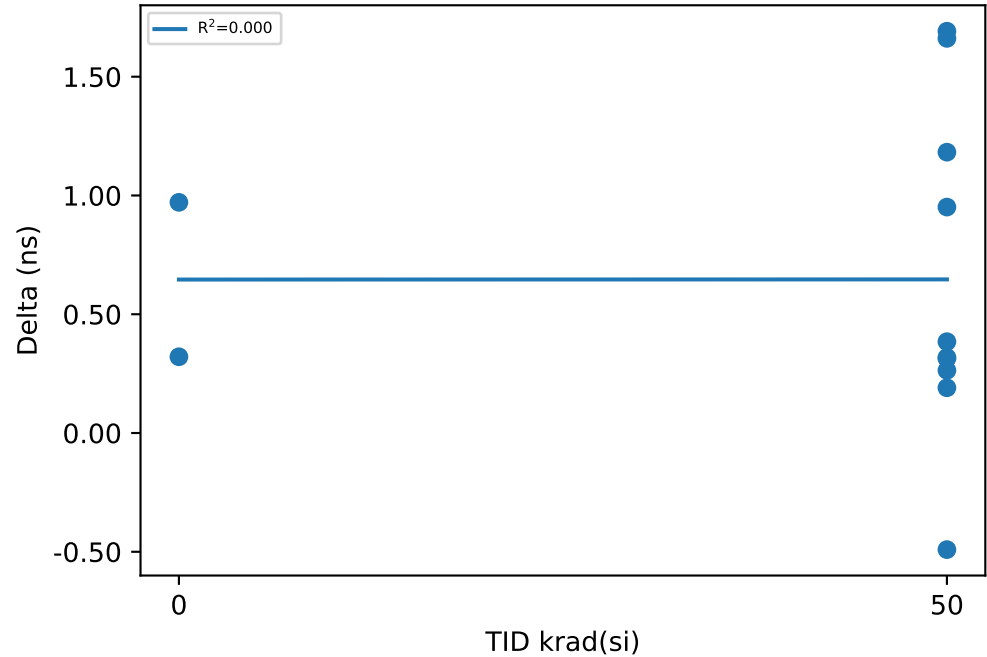
TID vs Result Stats



Test Results (Upper Limit = 115.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	62.401	63.372	0.9711
2	0	Correlation	62.704	63.025	0.321
4	50	Bias	63.494	64.445	0.9512
6	50	Bias	63.228	63.546	0.318
7	50	Bias	63.354	65.046	1.6916
8	50	Bias	63.346	65.007	1.6614
9	50	Bias	64.091	64.476	0.3845
11	50	Unbias	62.668	62.177	-0.4908
12	50	Unbias	61.896	63.078	1.1823
13	50	Unbias	62.456	62.72	0.2638
14	50	Unbias	64.003	64.318	0.3144
15	50	Unbias	62.196	62.387	0.1905

TID vs Post - Pre Exposure Delta

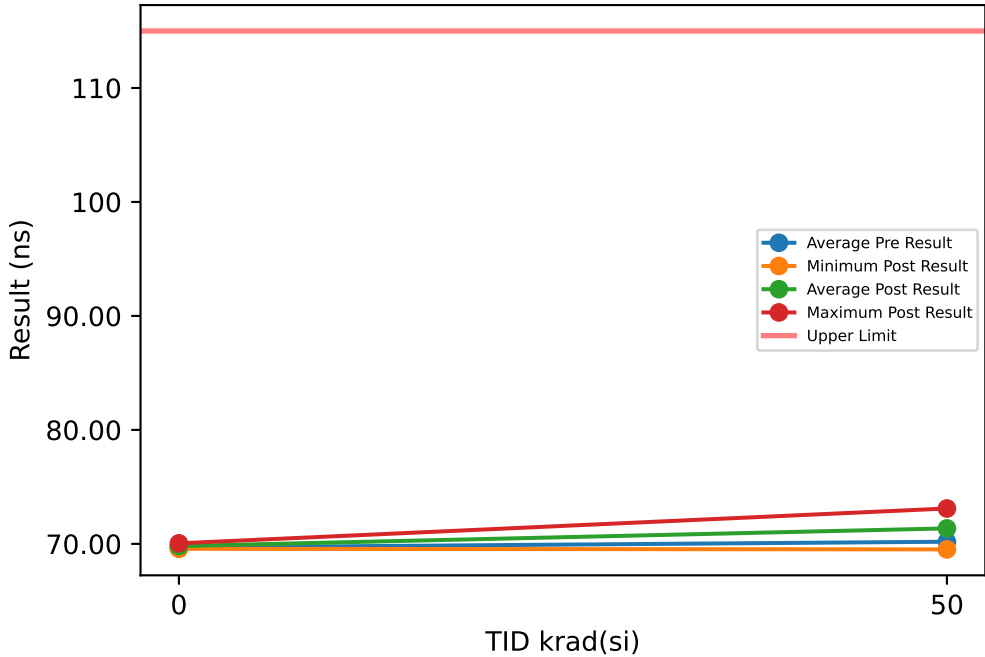


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	62.401	62.553	62.704	0.21397	63.025	63.199	63.372	0.24572	0.321	0.64605	0.9711	0.45969
50	61.896	63.073	64.091	0.74208	62.177	63.72	65.046	1.0786	-0.4908	0.64669	1.6916	0.70213

Device Test: 28.29 CS_ILIM_DELAY(TIMING|DELAY/CS/4.5/4.5/0/0/4.5/1MHz//@CS_ILIM_DELAY)

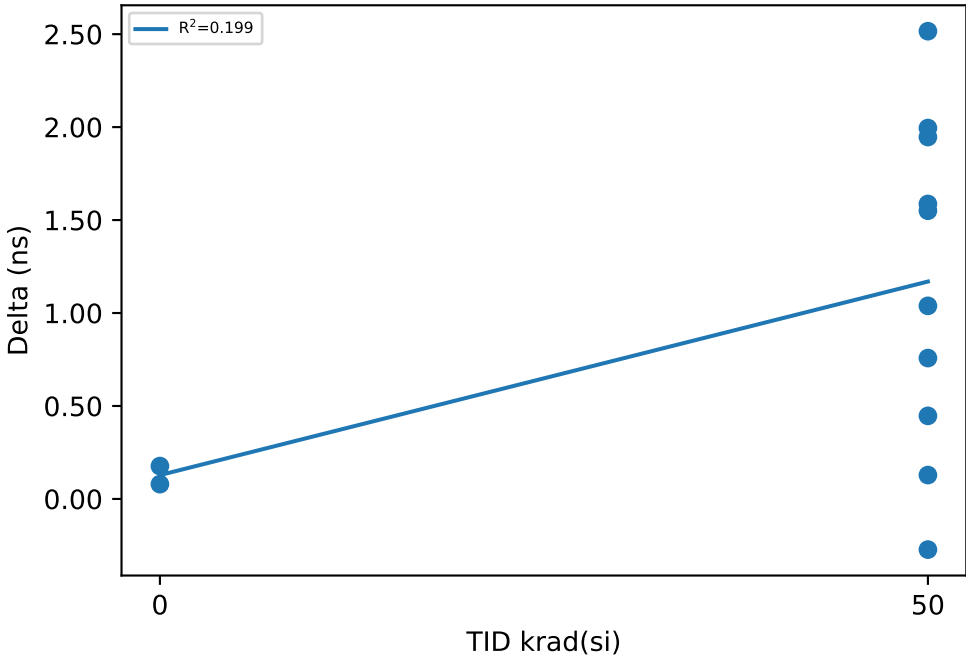
TID vs Result Stats



Test Results (Upper Limit = 115.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	69.871	70.048	0.1768
2	0	Correlation	69.489	69.568	0.0795
4	50	Bias	69.917	72.433	2.5159
6	50	Bias	70.237	71.788	1.5502
7	50	Bias	70.12	72.066	1.9467
8	50	Bias	71.518	73.105	1.5866
9	50	Bias	70.318	72.313	1.995
11	50	Unbias	69.523	70.562	1.0385
12	50	Unbias	69.387	69.516	0.1284
13	50	Unbias	69.788	69.515	-0.2725
14	50	Unbias	71.306	71.753	0.4468
15	50	Unbias	69.773	70.531	0.7577

TID vs Post - Pre Exposure Delta

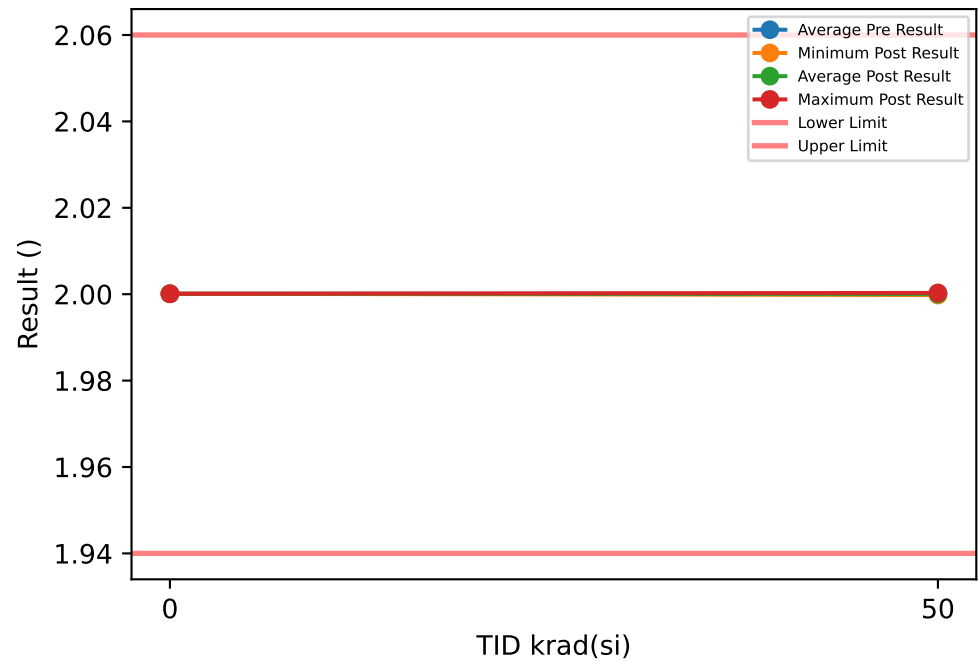


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	69.489	69.68	69.871	0.27019	69.568	69.808	70.048	0.33899	0.0795	0.12815	0.1768	0.068801
50	69.387	70.189	71.518	0.70964	69.515	71.358	73.105	1.2503	-0.2725	1.1693	2.5159	0.89997

Device Test: 28.3 C_CS_R(LEVEL|RATIO/CS/12/12/0/0/5/500kHz//@C_CS_R)

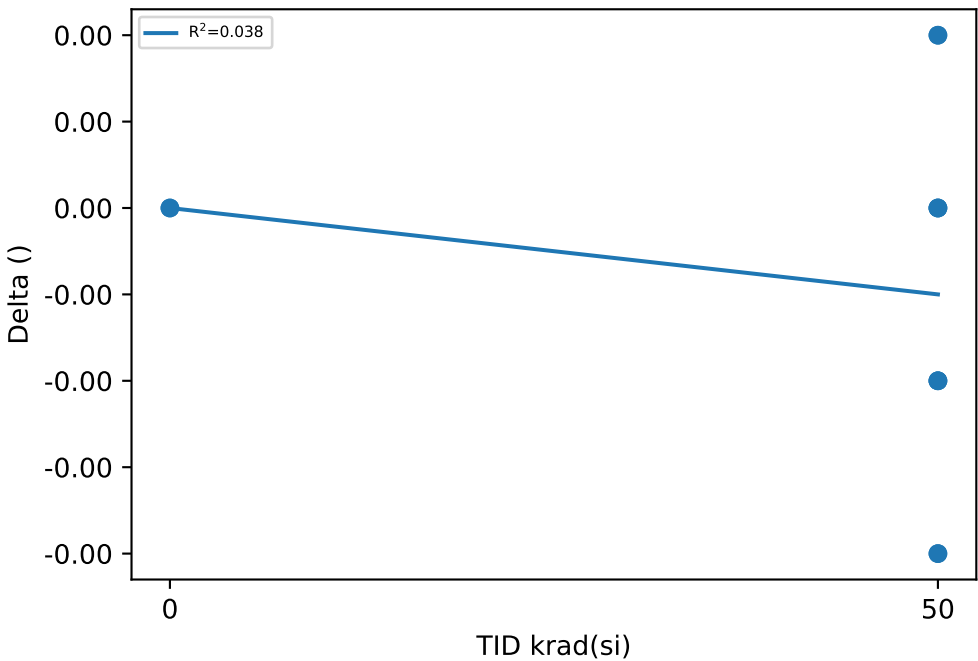
TID vs Result Stats



Test Results (Lower Limit = 1.94, Upper Limit = 2.06 (ranging from 0 to 50))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	2.0001	2.0001	0
2	0	Correlation	2.0001	2.0001	0
4	50	Bias	2.0001	1.9999	-0.0002
6	50	Bias	2	2	0
7	50	Bias	2.0001	2	-0.0001
8	50	Bias	2.0001	1.9999	-0.0002
9	50	Bias	2.0001	2	-0.0001
11	50	Unbias	2.0002	2.0003	0.0001
12	50	Unbias	2.0001	2.0001	0
13	50	Unbias	2	2.0001	0.0001
14	50	Unbias	1.9999	1.9998	-0.0001
15	50	Unbias	2.0001	2.0001	0

TID vs Post - Pre Exposure Delta

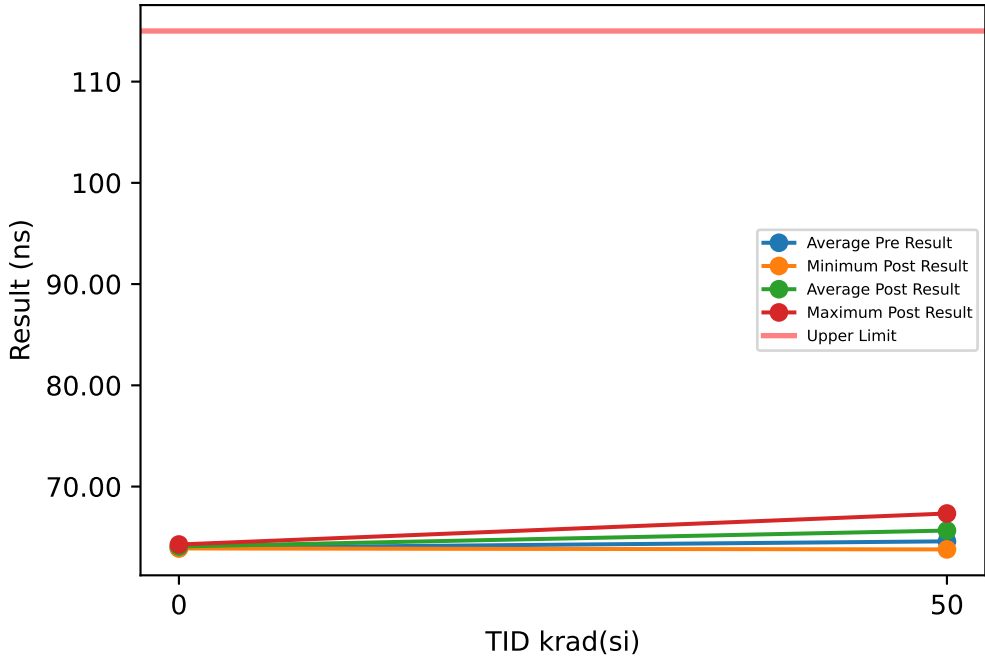


Test Statistics (ranging from 0 to 50)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.0001	2.0001	2.0001	0	2.0001	2.0001	2.0001	0	0	0	0	0
50	1.9999	2.0001	2.0002	8.2327e-05	1.9998	2	2.0003	0.00013984	-0.0002	-5e-05	0.0001	0.00010801

Device Test: 28.30 CS_ILIM_DELAY(TIMING|DELAY/CS/5/5/0/0/5/1MHz//@CS_ILIM_DELAY)

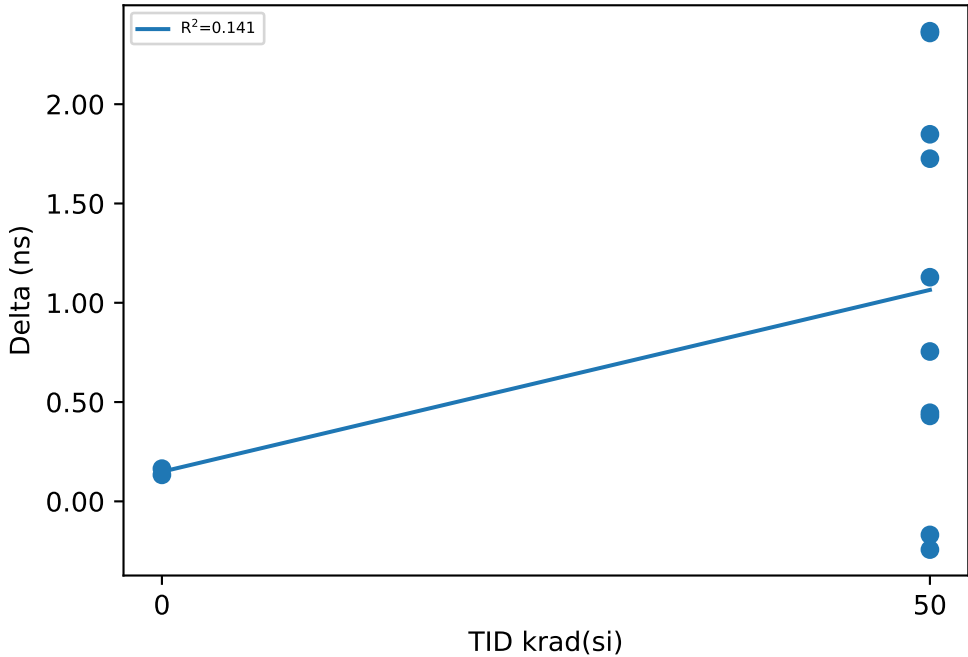
TID vs Result Stats



Test Results (Upper Limit = 115.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	63.722	63.886	0.1648
2	0	Correlation	64.144	64.278	0.1334
4	50	Bias	64.311	66.037	1.7257
6	50	Bias	65.152	65.907	0.7546
7	50	Bias	64.701	66.55	1.8485
8	50	Bias	64.76	67.118	2.3586
9	50	Bias	64.972	67.34	2.3676
11	50	Unbias	64.177	64.607	0.4303
12	50	Unbias	63.963	63.794	-0.1689
13	50	Unbias	64.495	64.253	-0.2429
14	50	Unbias	65.734	66.18	0.4462
15	50	Unbias	63.641	64.77	1.1287

TID vs Post - Pre Exposure Delta

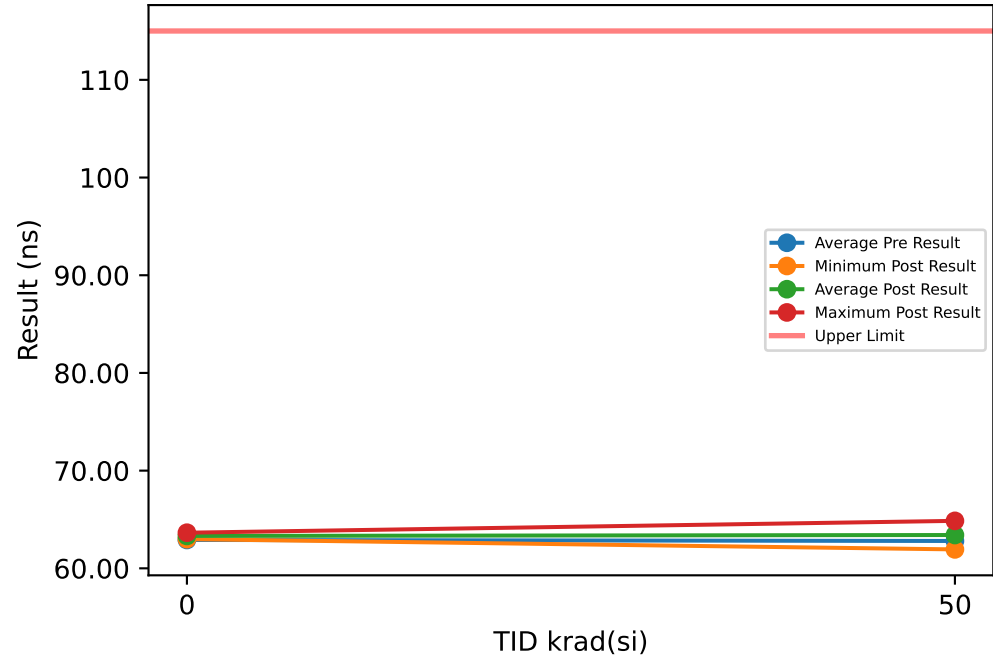


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	63.722	63.933	64.144	0.29889	63.886	64.082	64.278	0.27669	0.1334	0.1491	0.1648	0.022203
50	63.641	64.591	65.734	0.61109	63.794	65.656	67.34	1.2281	-0.2429	1.0648	2.3676	0.9741

Device Test: 28.31 CS_ILIM_DELAY(TIMING|DELAY/CS/12/12/0/0/5/1MHz//@CS_ILIM_DELAY)

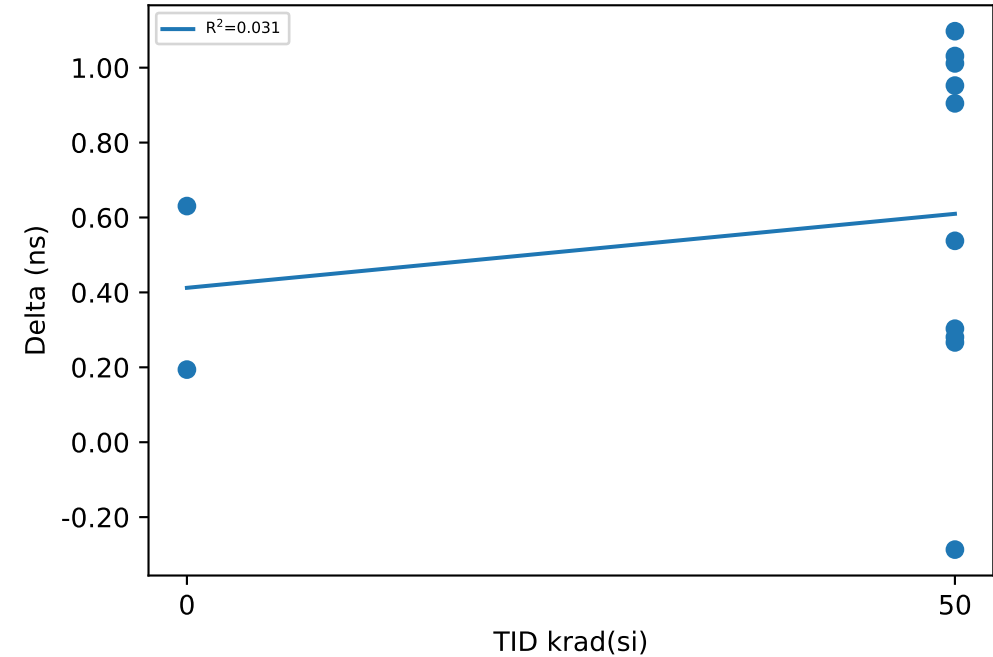
TID vs Result Stats



Test Results (Upper Limit = 115.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	62.793	62.987	0.1939
2	0	Correlation	63.015	63.646	0.6305
4	50	Bias	62.526	63.43	0.9047
6	50	Bias	62.971	63.509	0.5377
7	50	Bias	63.057	64.068	1.0114
8	50	Bias	63.761	64.858	1.0974
9	50	Bias	63.099	64.13	1.0311
11	50	Unbias	61.635	61.938	0.3031
12	50	Unbias	61.811	62.764	0.9522
13	50	Unbias	62.87	62.584	-0.2867
14	50	Unbias	63.718	63.984	0.2664
15	50	Unbias	62.548	62.829	0.2807

TID vs Post - Pre Exposure Delta

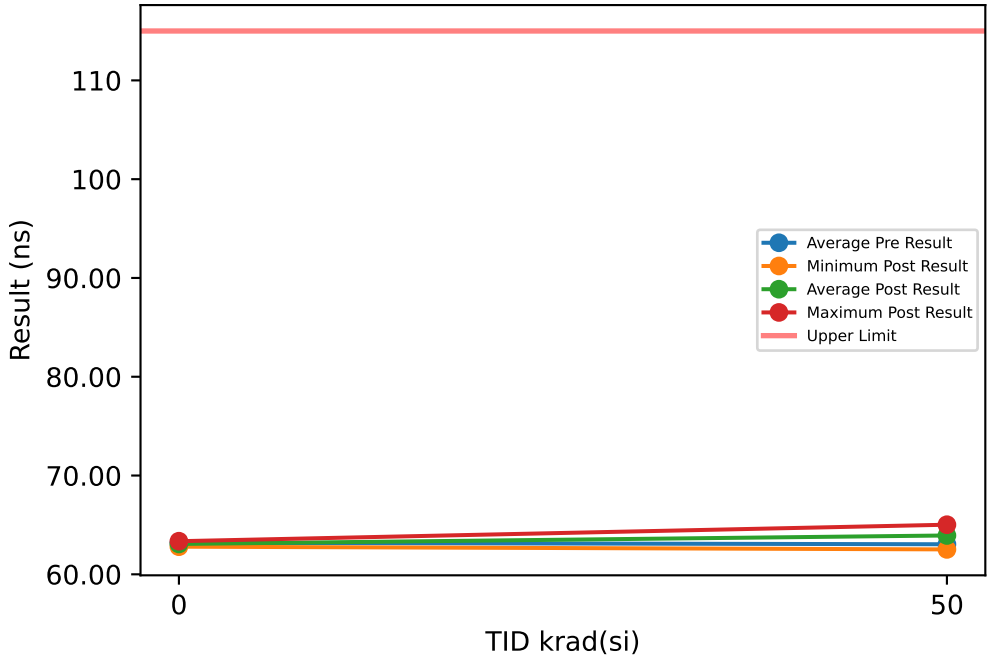


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	62.793	62.904	63.015	0.15733	62.987	63.316	63.646	0.46605	0.1939	0.4122	0.6305	0.30872
50	61.635	62.8	63.761	0.70156	61.938	63.409	64.858	0.88163	-0.2867	0.6098	1.0974	0.46067

Device Test: 28.32 CS_ILIM_DELAY(TIMING|DELAY/CS/14/14/0/0/5/1MHz//@CS_ILIM_DELAY)

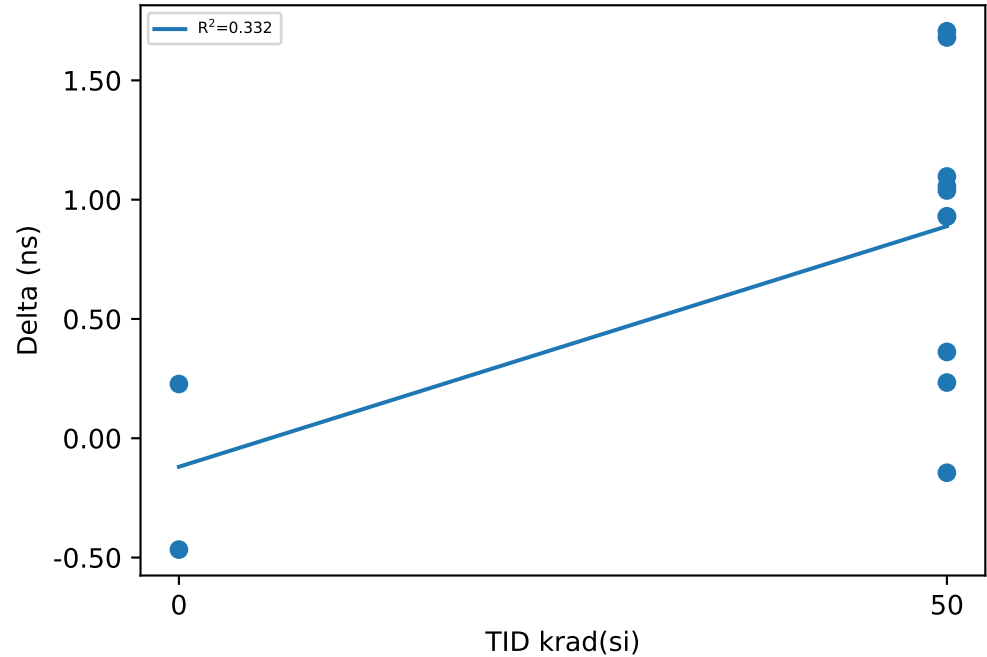
TID vs Result Stats



Test Results (Upper Limit = 115.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	63.124	63.351	0.2274
2	0	Correlation	63.263	62.797	-0.4667
4	50	Bias	62.717	64.423	1.7061
6	50	Bias	62.577	63.633	1.0564
7	50	Bias	63.995	64.229	0.2335
8	50	Bias	63.341	65.021	1.6797
9	50	Bias	64.023	64.954	0.9303
11	50	Unbias	62.512	62.874	0.3617
12	50	Unbias	62.667	62.522	-0.1446
13	50	Unbias	62.51	63.439	0.929
14	50	Unbias	63.923	65.02	1.0972
15	50	Unbias	62.159	63.197	1.0384

TID vs Post - Pre Exposure Delta

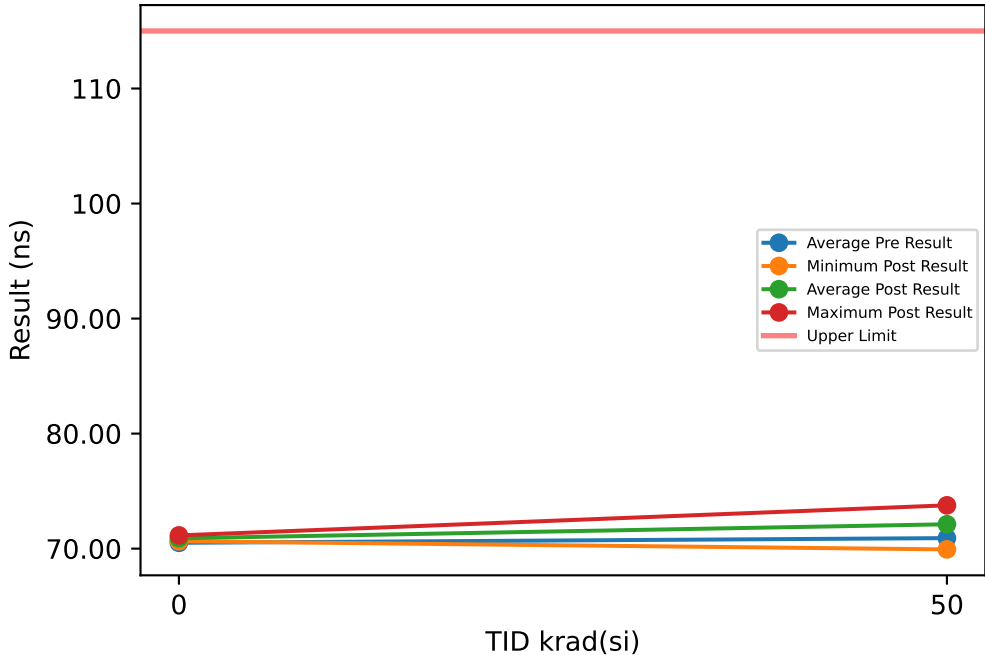


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	63.124	63.194	63.263	0.0985	62.797	63.074	63.351	0.3923	-0.4667	-0.11965	0.2274	0.4908
50	62.159	63.042	64.023	0.71061	62.522	63.931	65.021	0.92631	-0.1446	0.88877	1.7061	0.5931

Device Test: 28.33 CS_ILIM_DELAY(TIMING|DELAY/CS/4.5/4.5/0/1000/4.5/100kHz//@CS_ILIM_DELAY)

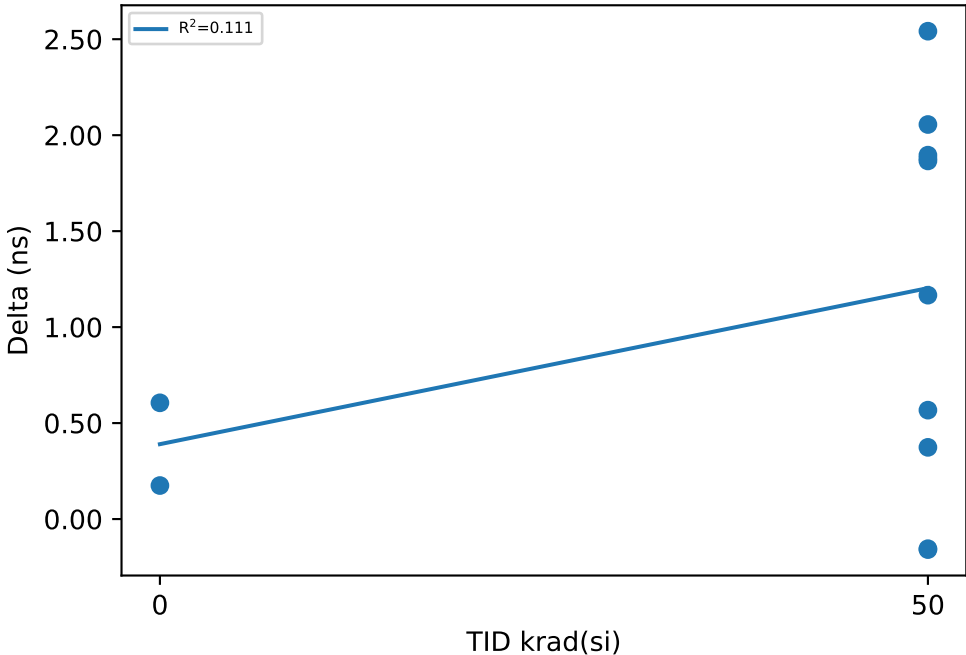
TID vs Result Stats



Test Results (Upper Limit = 115.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	70.038	70.643	0.6056
2	0	Correlation	70.975	71.15	0.1747
4	50	Bias	71.355	73.233	1.8783
6	50	Bias	70.498	72.393	1.8959
7	50	Bias	71.54	73.406	1.8658
8	50	Bias	71.673	73.728	2.0556
9	50	Bias	71.222	73.764	2.5417
11	50	Unbias	69.525	70.692	1.1664
12	50	Unbias	70.092	69.933	-0.1591
13	50	Unbias	70.633	71.007	0.3736
14	50	Unbias	72.04	72.608	0.5674
15	50	Unbias	70.56	70.406	-0.1544

TID vs Post - Pre Exposure Delta

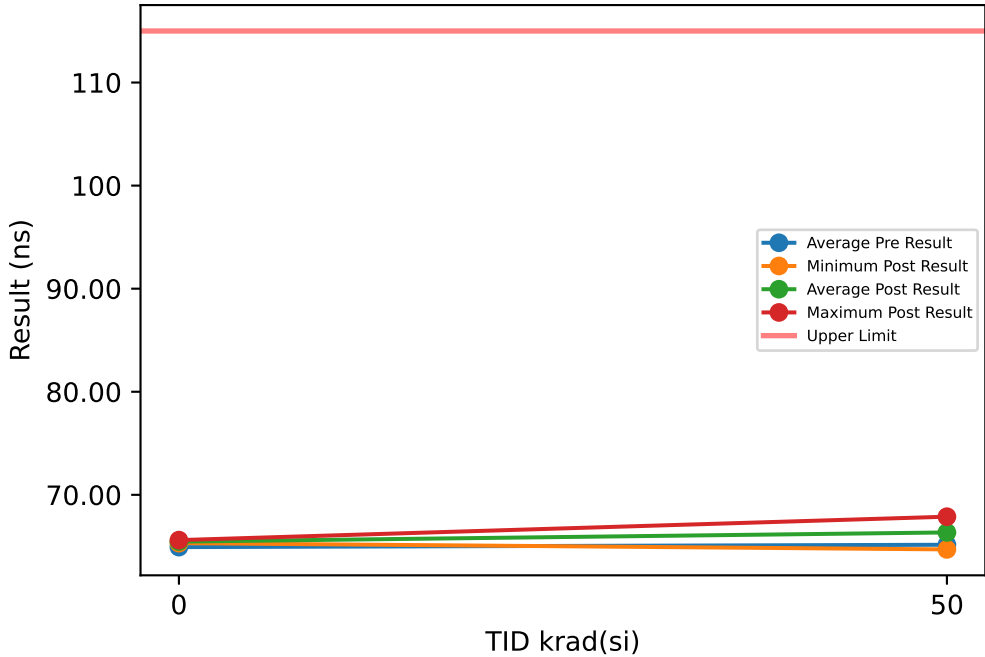


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	70.038	70.506	70.975	0.66277	70.643	70.897	71.15	0.35808	0.1747	0.39015	0.6056	0.30469
50	69.525	70.914	72.04	0.78223	69.933	72.117	73.764	1.4718	-0.1591	1.2031	2.5417	0.98238

Device Test: 28.34 CS_ILIM_DELAY(TIMING|DELAY/CS/5/5/0/1000/5/100kHz//@CS_ILIM_DELAY)

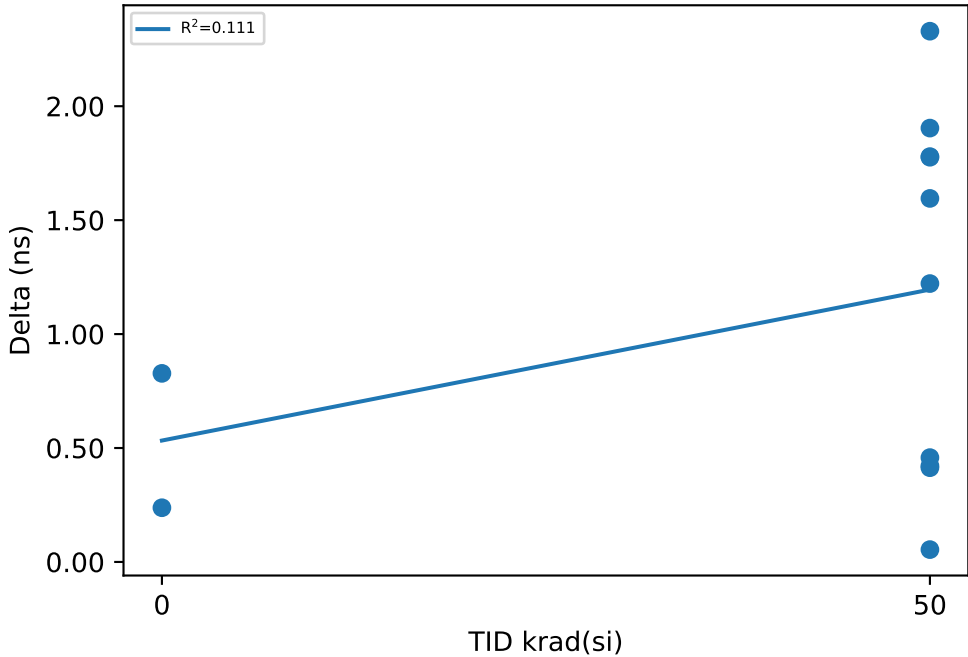
TID vs Result Stats



Test Results (Upper Limit = 115.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	65.077	65.315	0.2379
2	0	Correlation	64.779	65.607	0.8276
4	50	Bias	65.581	67.485	1.904
6	50	Bias	65.111	67.44	2.3292
7	50	Bias	65.446	67.041	1.5954
8	50	Bias	66.1	67.879	1.7788
9	50	Bias	65.627	67.403	1.7761
11	50	Unbias	64.87	65.328	0.4579
12	50	Unbias	64.652	64.706	0.0542
13	50	Unbias	63.862	65.084	1.2217
14	50	Unbias	65.901	66.323	0.4217
15	50	Unbias	64.413	64.827	0.4136

TID vs Post - Pre Exposure Delta

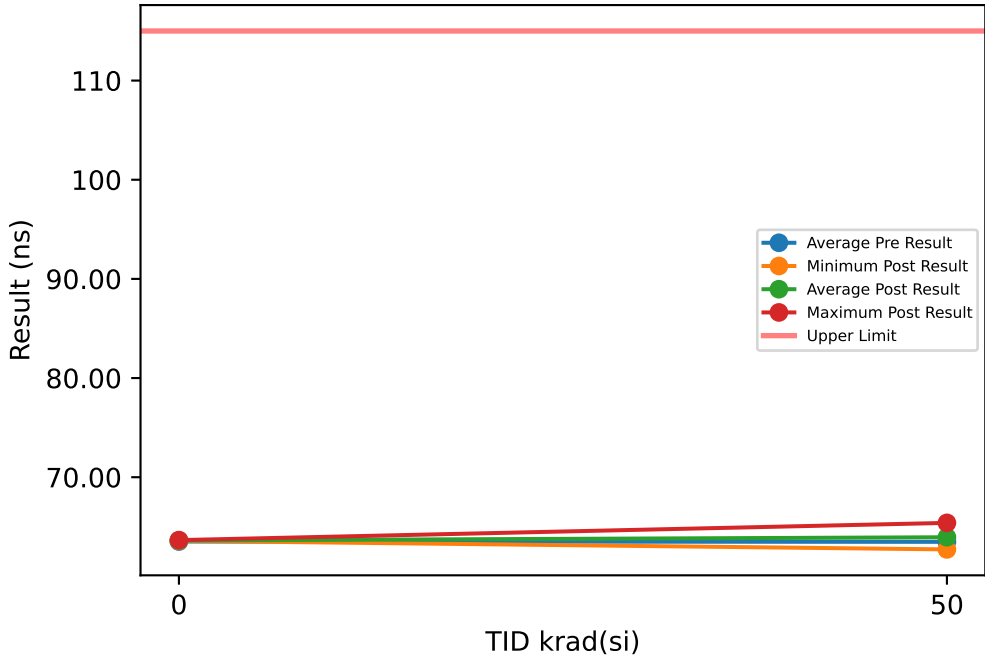


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	64.779	64.928	65.077	0.21029	65.315	65.461	65.607	0.20669	0.2379	0.53275	0.8276	0.41698
50	63.862	65.156	66.1	0.70702	64.706	66.352	67.879	1.2506	0.0542	1.1953	2.3292	0.79456

Device Test: 28.35 CS_ILIM_DELAY(TIMING|DELAY/CS/12/12/0/1000/5/100kHz//@CS_ILIM_DELAY)

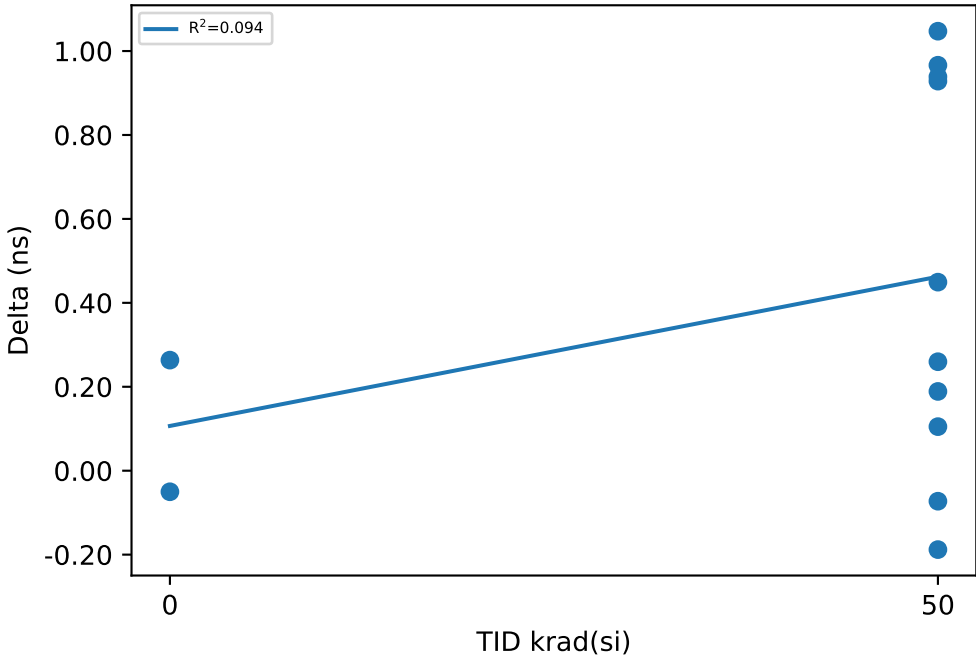
TID vs Result Stats



Test Results (Upper Limit = 115.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	63.393	63.657	0.2635
2	0	Correlation	63.635	63.585	-0.0502
4	50	Bias	63.158	64.124	0.9662
6	50	Bias	63.611	64.061	0.4493
7	50	Bias	64.392	64.652	0.2597
8	50	Bias	64.347	65.394	1.0473
9	50	Bias	63.697	64.636	0.9387
11	50	Unbias	62.909	62.721	-0.188
12	50	Unbias	62.971	62.898	-0.0727
13	50	Unbias	62.925	63.03	0.105
14	50	Unbias	64.283	64.472	0.1889
15	50	Unbias	62.537	63.465	0.9283

TID vs Post - Pre Exposure Delta

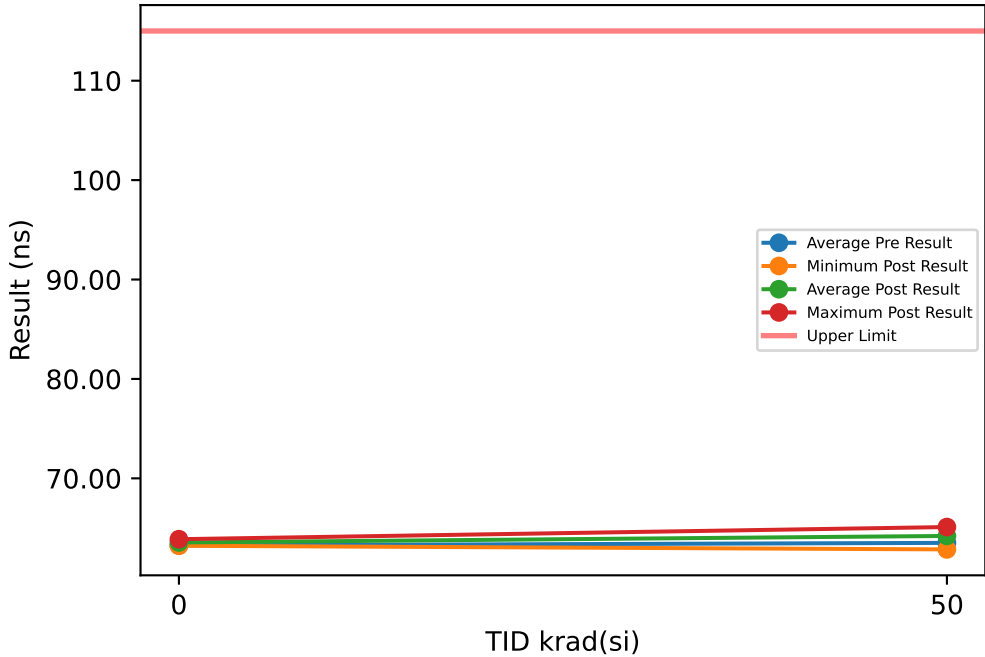


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	63.393	63.514	63.635	0.17098	63.585	63.621	63.657	0.050841	-0.0502	0.10665	0.2635	0.22182
50	62.537	63.483	64.392	0.68146	62.721	63.945	65.394	0.8859	-0.188	0.46227	1.0473	0.47058

Device Test: 28.36 CS_ILIM_DELAY(TIMING|DELAY/CS/14/14/0/1000/5/100kHz//@CS_ILIM_DELAY)

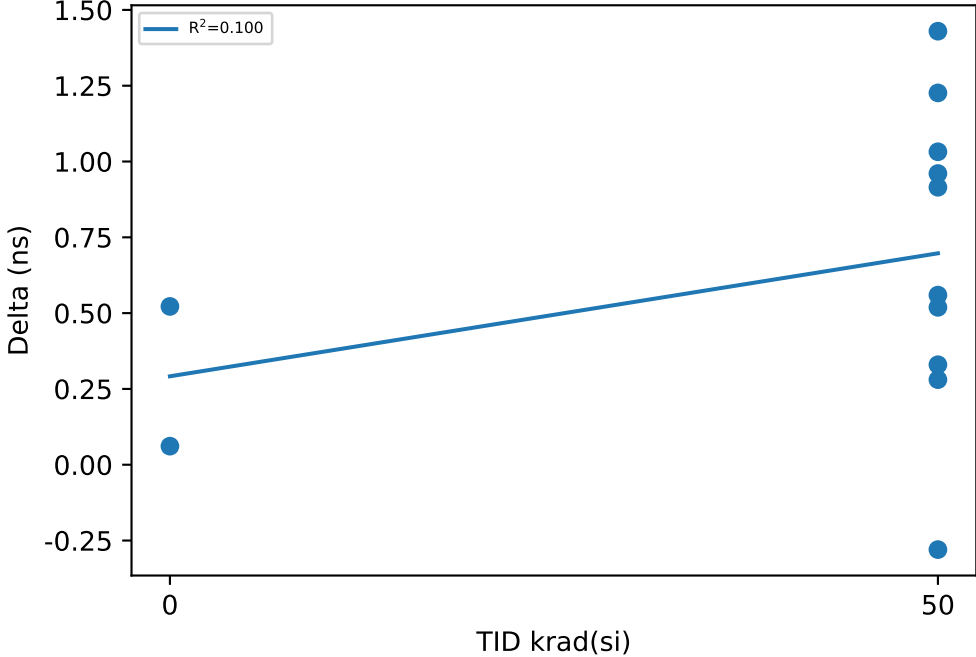
TID vs Result Stats



Test Results (Upper Limit = 115.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	63.357	63.879	0.5221
2	0	Correlation	63.157	63.218	0.0612
4	50	Bias	63.467	64.382	0.9151
6	50	Bias	63.909	64.469	0.5594
7	50	Bias	63.683	64.91	1.2263
8	50	Bias	64.07	65.102	1.0321
9	50	Bias	64.738	65.019	0.2806
11	50	Unbias	63.133	62.853	-0.2799
12	50	Unbias	62.62	63.139	0.5191
13	50	Unbias	62.04	63.47	1.4298
14	50	Unbias	64.632	64.962	0.3298
15	50	Unbias	62.795	63.755	0.9604

TID vs Post - Pre Exposure Delta

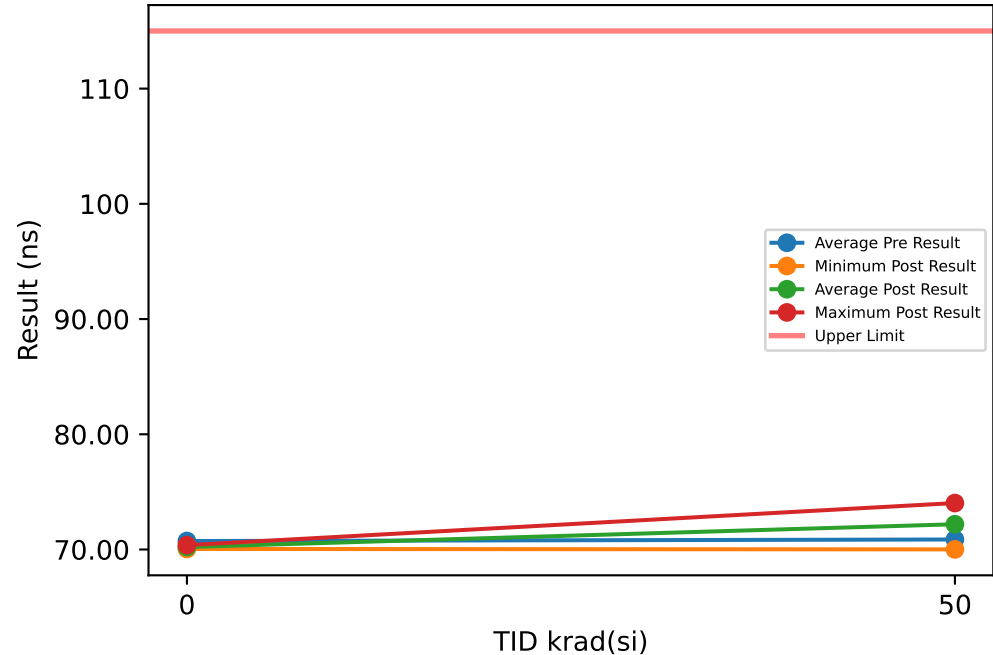


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	63.157	63.257	63.357	0.14121	63.218	63.549	63.879	0.46711	0.0612	0.29165	0.5221	0.32591
50	62.04	63.509	64.738	0.87415	62.853	64.206	65.102	0.83949	-0.2799	0.69727	1.4298	0.51203

Device Test: 28.37 CS_ILIM_DELAY(TIMING|DELAY/CS/4.5/4.5/0/1000/4.5/500kHz//@CS_ILIM_DELAY)

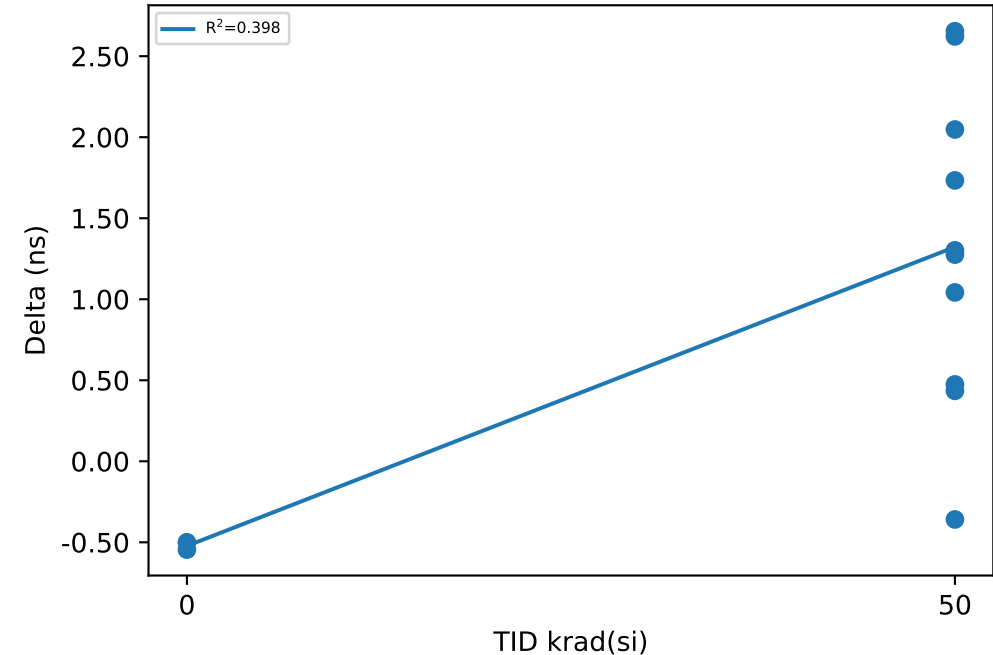
TID vs Result Stats



Test Results (Upper Limit = 115.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	70.547	70.047	-0.4998
2	0	Correlation	70.923	70.378	-0.545
4	50	Bias	71.34	72.382	1.042
6	50	Bias	71.408	73.141	1.7333
7	50	Bias	70.782	73.404	2.6218
8	50	Bias	71.024	73.678	2.6542
9	50	Bias	71.983	74.031	2.0476
11	50	Unbias	70.368	70.009	-0.359
12	50	Unbias	69.399	70.674	1.2753
13	50	Unbias	70.633	71.107	0.4745
14	50	Unbias	71.174	72.476	1.3019
15	50	Unbias	70.574	71.009	0.4346

TID vs Post - Pre Exposure Delta

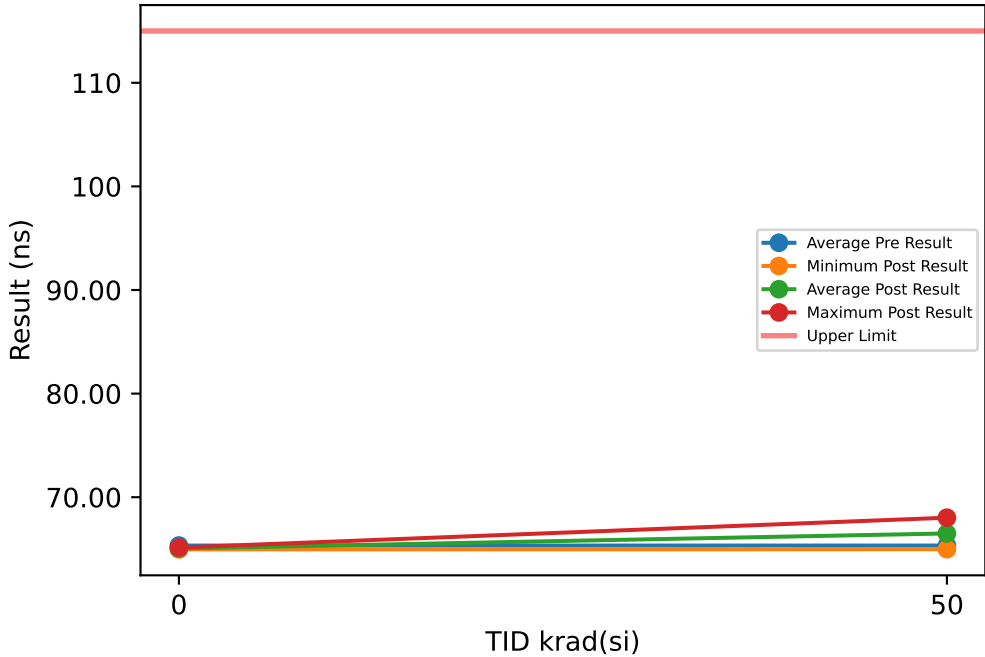


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	70.547	70.735	70.923	0.26615	70.047	70.213	70.378	0.23419	-0.545	-0.5224	-0.4998	0.031961
50	69.399	70.868	71.983	0.70174	70.009	72.191	74.031	1.4032	-0.359	1.3226	2.6542	0.97595

Device Test: 28.38 CS_ILIM_DELAY(TIMING|DELAY/CS/5/5/0/1000/5/500kHz//@CS_ILIM_DELAY)

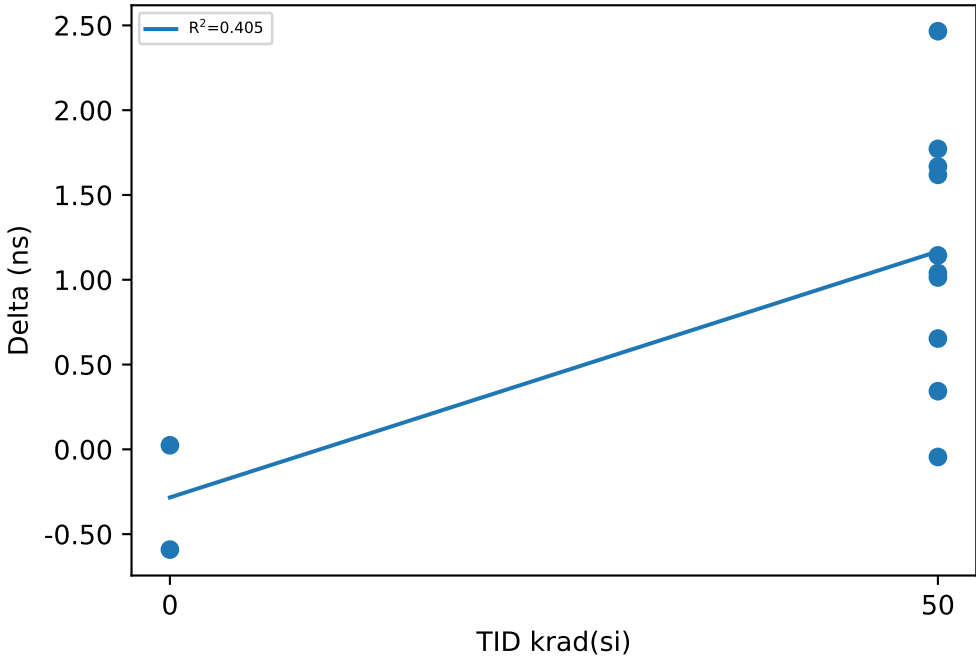
TID vs Result Stats



Test Results (Upper Limit = 115.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	65.114	65.138	0.0239
2	0	Correlation	65.554	64.963	-0.5912
4	50	Bias	65.666	66.679	1.0134
6	50	Bias	65.029	67.494	2.4658
7	50	Bias	65.435	67.054	1.6187
8	50	Bias	66.098	67.87	1.7718
9	50	Bias	66.354	68.022	1.668
11	50	Unbias	64.2	65.24	1.0399
12	50	Unbias	64.598	65.251	0.6533
13	50	Unbias	64.358	65.502	1.1436
14	50	Unbias	66.583	66.926	0.3429
15	50	Unbias	65.025	64.98	-0.045

TID vs Post - Pre Exposure Delta

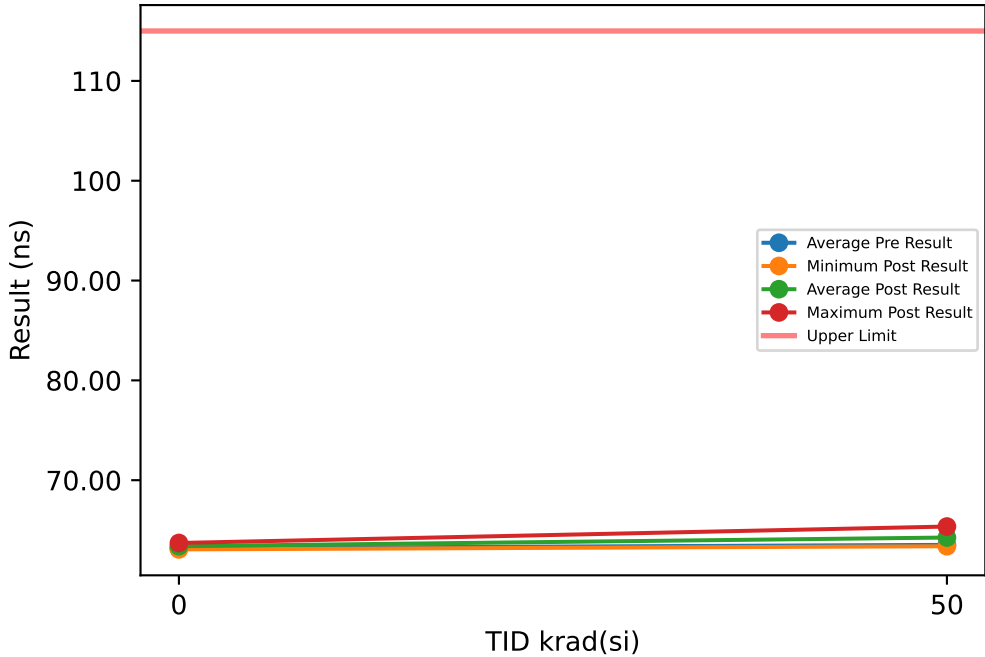


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	65.114	65.334	65.554	0.31099	64.963	65.051	65.138	0.12396	-0.5912	-0.28365	0.0239	0.43494
50	64.2	65.334	66.583	0.83504	64.98	66.502	68.022	1.1623	-0.045	1.1672	2.4658	0.74237

Device Test: 28.39 CS_ILIM_DELAY(TIMING|DELAY/CS/12/12/0/1000/5/500kHz//@CS_ILIM_DELAY)

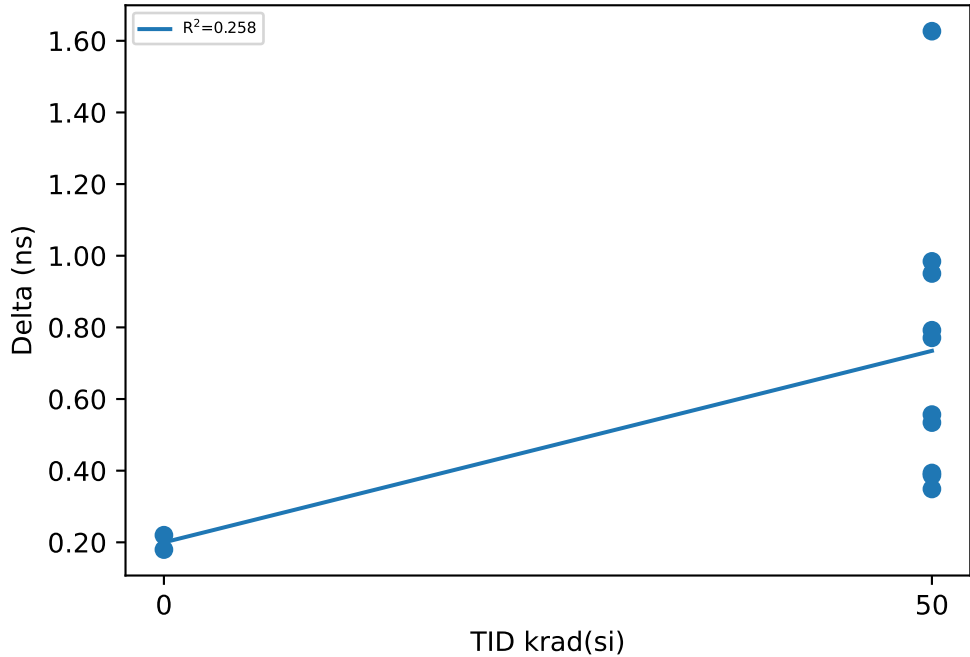
TID vs Result Stats



Test Results (Upper Limit = 115.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	63.489	63.709	0.2199
2	0	Correlation	62.887	63.067	0.1797
4	50	Bias	63.302	64.072	0.7708
6	50	Bias	63.95	64.506	0.5566
7	50	Bias	63.826	64.618	0.7921
8	50	Bias	63.73	65.356	1.6268
9	50	Bias	64.343	64.737	0.3936
11	50	Unbias	62.867	63.401	0.5342
12	50	Unbias	62.996	63.383	0.3873
13	50	Unbias	62.728	63.712	0.9843
14	50	Unbias	64.917	65.266	0.3489
15	50	Unbias	62.546	63.497	0.9504

TID vs Post - Pre Exposure Delta

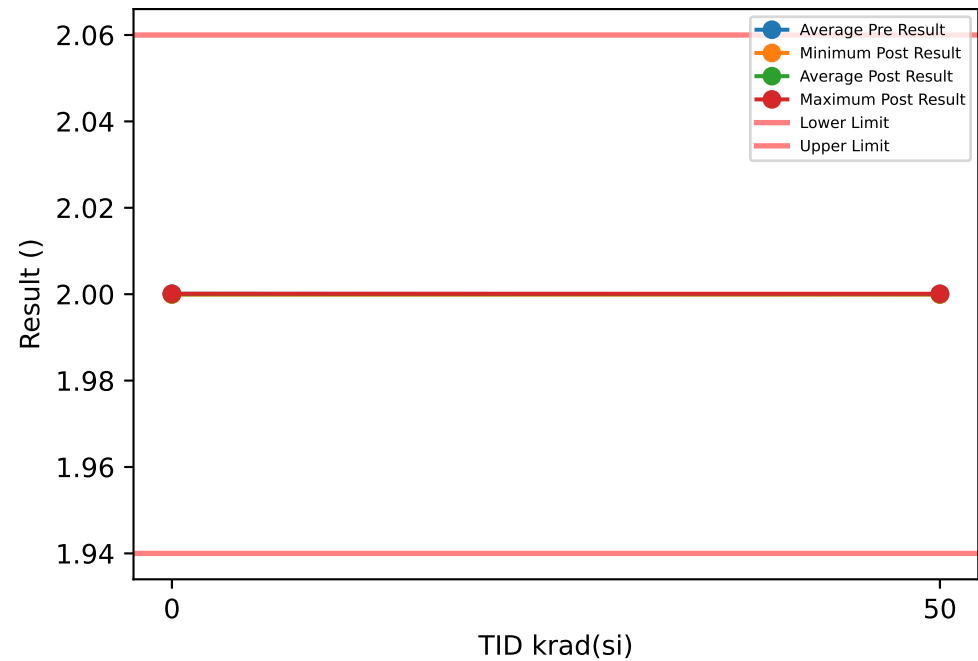


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	62.887	63.188	63.489	0.42582	63.067	63.388	63.709	0.45425	0.1797	0.1998	0.2199	0.028426
50	62.546	63.52	64.917	0.76582	63.383	64.255	65.356	0.74956	0.3489	0.7345	1.6268	0.38974

Device Test: 28.4 C_CS_R(LEVEL|RATIO/CS/14/14/0/0/5/500kHz//@C_CS_R)

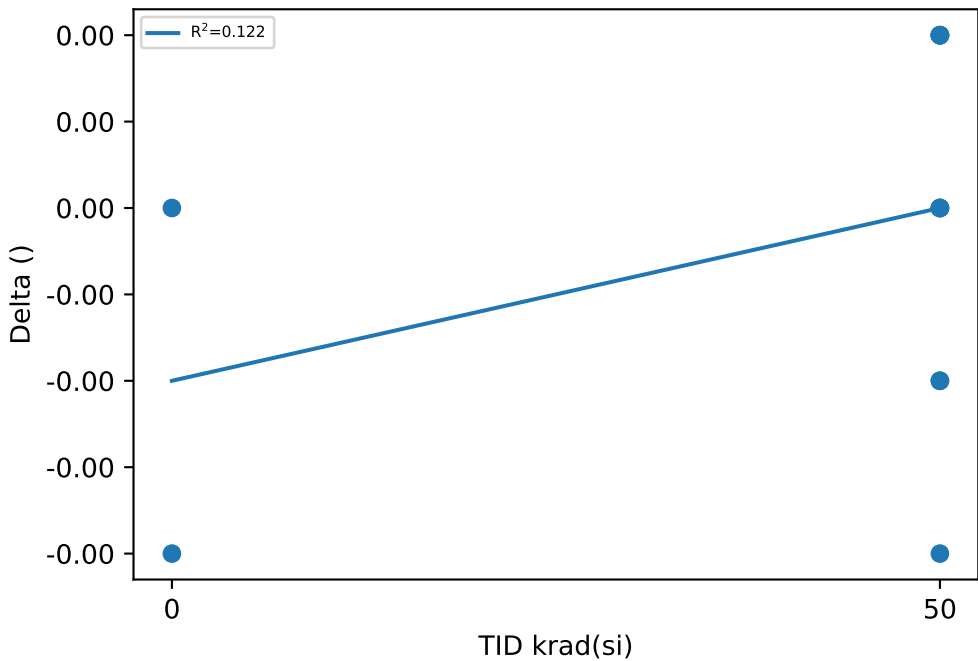
TID vs Result Stats



Test Results (Lower Limit = 1.94, Upper Limit = 2.06 (ranging from 0 to 50))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	2.0001	2.0001	0
2	0	Correlation	2.0001	1.9999	-0.0002
4	50	Bias	1.9999	2	0.0001
6	50	Bias	2	2	0
7	50	Bias	2.0001	2.0001	0
8	50	Bias	2	2.0001	0.0001
9	50	Bias	1.9999	2	0.0001
11	50	Unbias	2.0001	2	-0.0001
12	50	Unbias	2.0001	2	-0.0001
13	50	Unbias	2	2	0
14	50	Unbias	1.9999	2	0.0001
15	50	Unbias	2.0001	1.9999	-0.0002

TID vs Post - Pre Exposure Delta

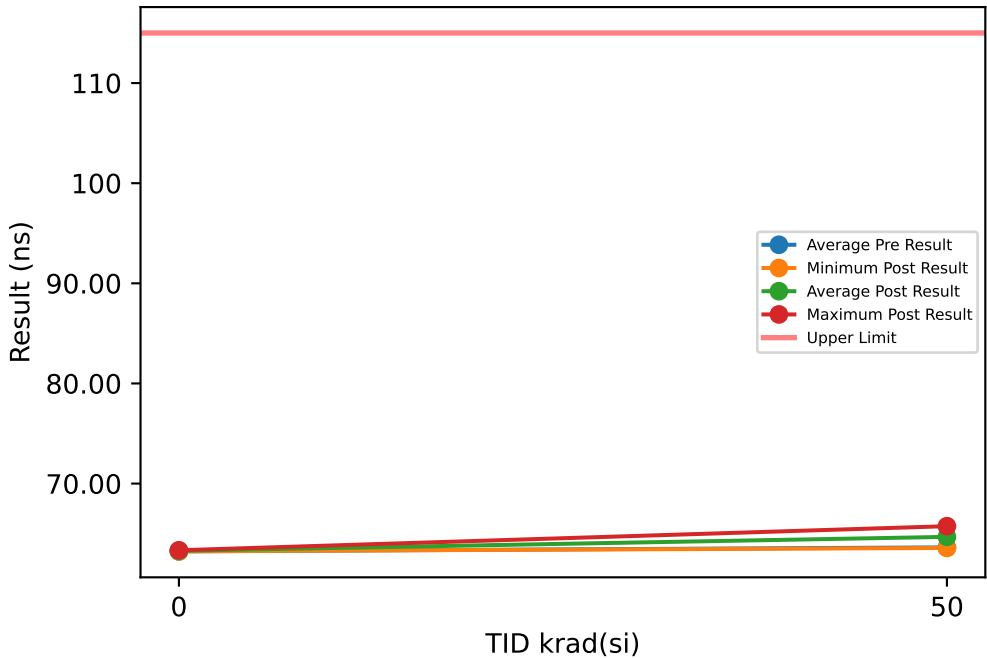


Test Statistics (ranging from 0 to 50)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.0001	2.0001	2.0001	0	1.9999	2	2.0001	0.00014142	-0.0002	-0.0001	0	0.00014142
50	1.9999	2	2.0001	8.756e-05	1.9999	2	2.0001	5.6765e-05	-0.0002	-4.4409e-17	0.0001	0.00010541

Device Test: 28.40 CS_ILIM_DELAY(TIMING|DELAY/CS/14/14/0/1000/5/500kHz//@CS_ILIM_DELAY)

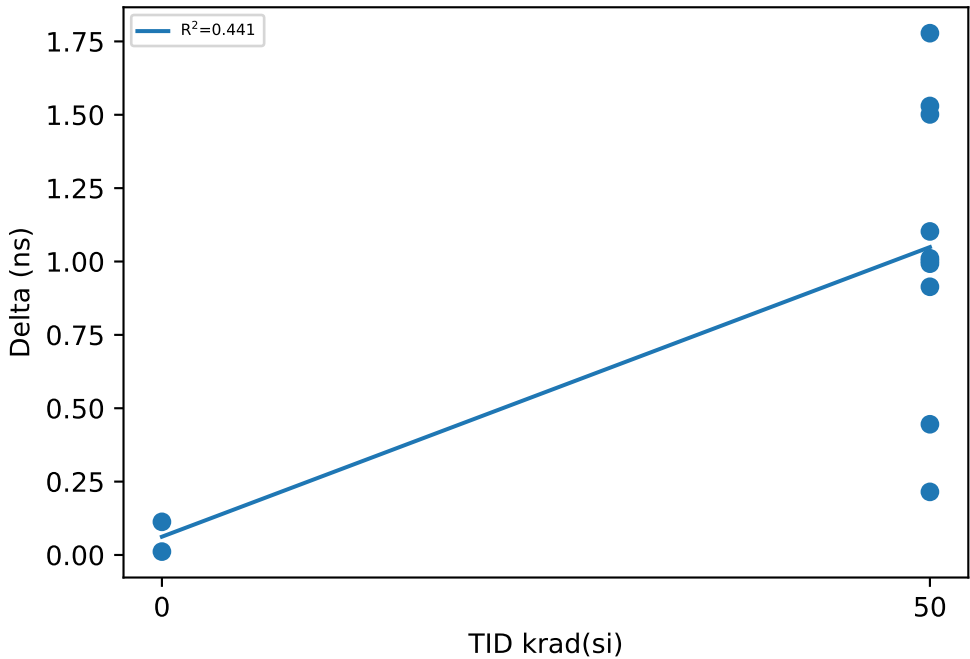
TID vs Result Stats



Test Results (Upper Limit = 115.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	63.126	63.239	0.1129
2	0	Correlation	63.329	63.34	0.0115
4	50	Bias	63.458	64.46	1.002
6	50	Bias	63.261	64.762	1.5012
7	50	Bias	64.566	65.558	0.9926
8	50	Bias	64.156	65.686	1.53
9	50	Bias	63.967	65.745	1.778
11	50	Unbias	62.466	63.569	1.1025
12	50	Unbias	62.621	63.632	1.0109
13	50	Unbias	63.047	63.961	0.9139
14	50	Unbias	65.182	65.628	0.4454
15	50	Unbias	63.558	63.773	0.215

TID vs Post - Pre Exposure Delta

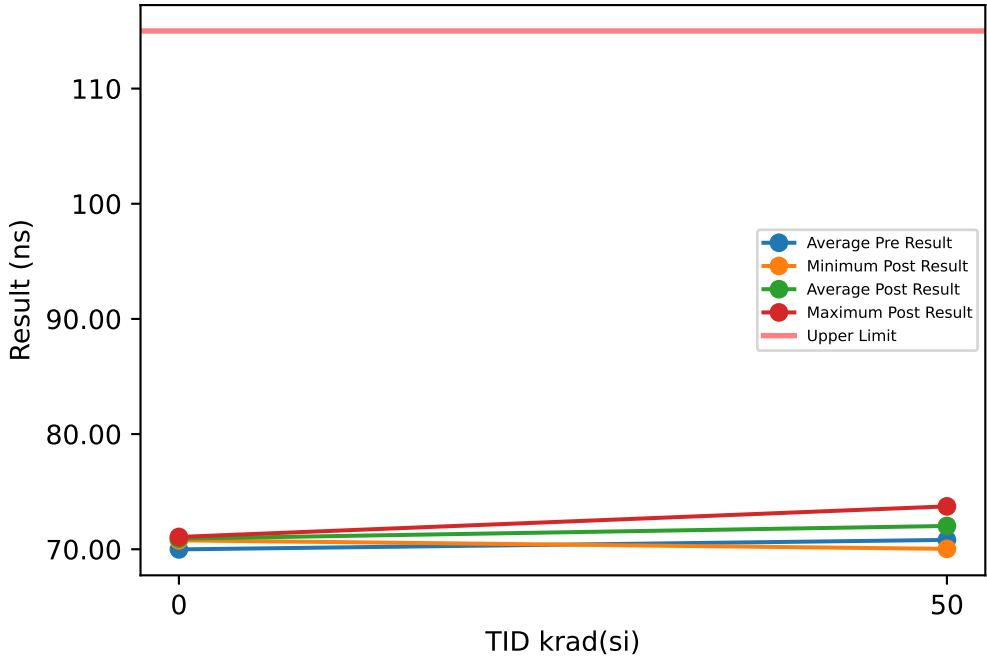


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	63.126	63.227	63.329	0.14361	63.239	63.289	63.34	0.071913	0.0115	0.0622	0.1129	0.071701
50	62.466	63.628	65.182	0.85364	63.569	64.677	65.745	0.91561	0.215	1.0492	1.778	0.47786

Device Test: 28.41 CS_ILIM_DELAY(TIMING|DELAY/CS/4.5/4.5/0/1000/4.5/1MHz//@CS_ILIM_DELAY)

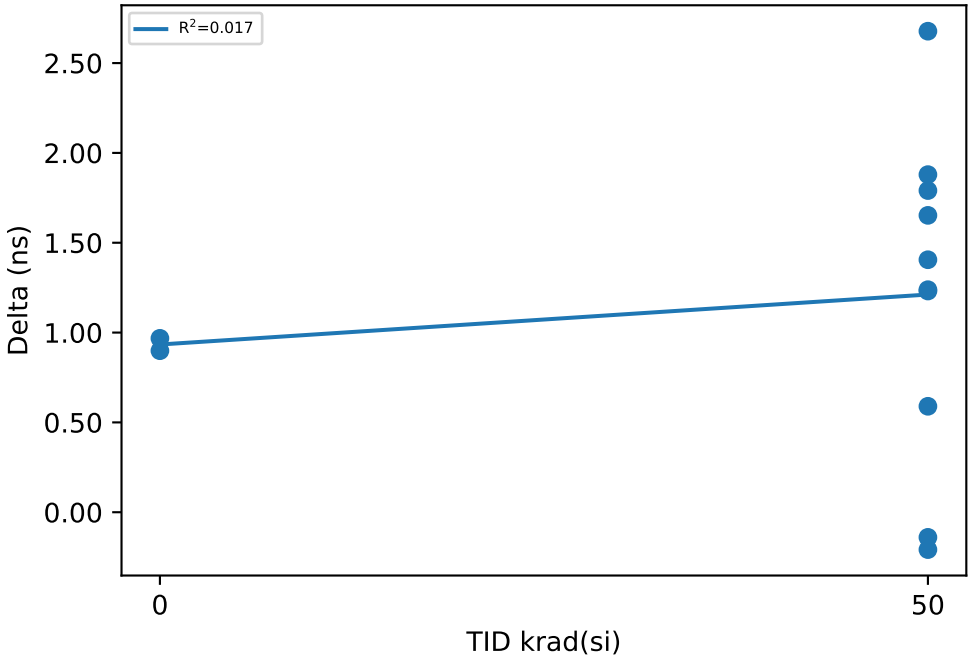
TID vs Result Stats



Test Results (Upper Limit = 115.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	69.806	70.774	0.968
2	0	Correlation	70.169	71.068	0.8991
4	50	Bias	71.296	73.175	1.8792
6	50	Bias	70.711	72.364	1.6524
7	50	Bias	71.553	72.791	1.2387
8	50	Bias	71.026	73.703	2.6775
9	50	Bias	71.932	73.723	1.7905
11	50	Unbias	69.501	70.732	1.2313
12	50	Unbias	69.445	70.034	0.5897
13	50	Unbias	69.953	71.358	1.4054
14	50	Unbias	72.088	71.948	-0.1398
15	50	Unbias	70.614	70.406	-0.208

TID vs Post - Pre Exposure Delta

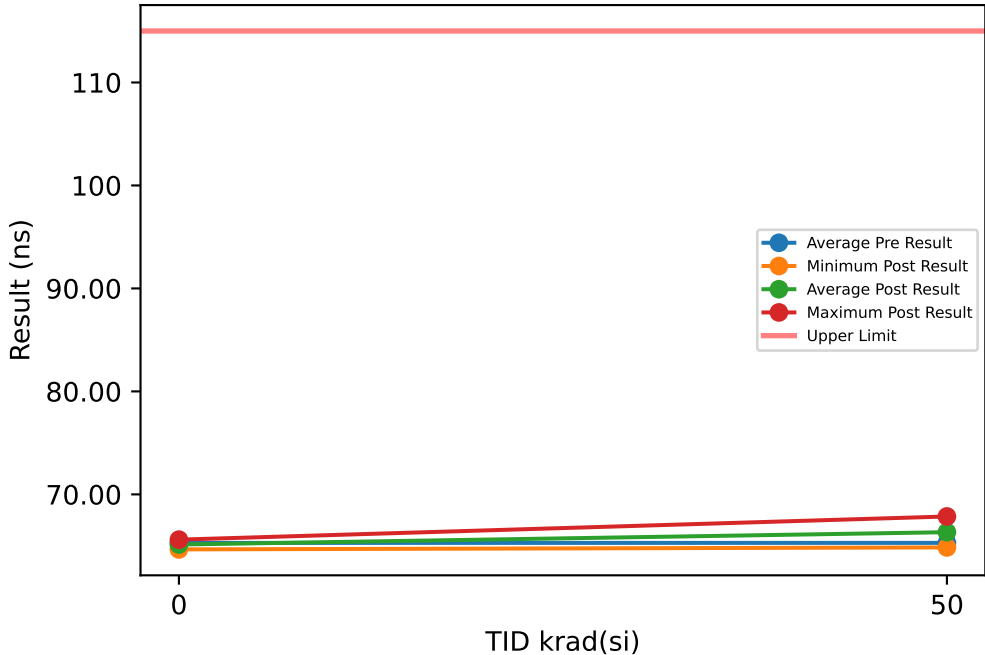


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	69.806	69.988	70.169	0.25661	70.774	70.921	71.068	0.20789	0.8991	0.93355	0.968	0.04872
50	69.445	70.812	72.088	0.94794	70.034	72.024	73.723	1.351	-0.208	1.2117	2.6775	0.90621

Device Test: 28.42 CS_ILIM_DELAY(TIMING|DELAY/CS/5/5/0/1000/5/1MHz//@CS_ILIM_DELAY)

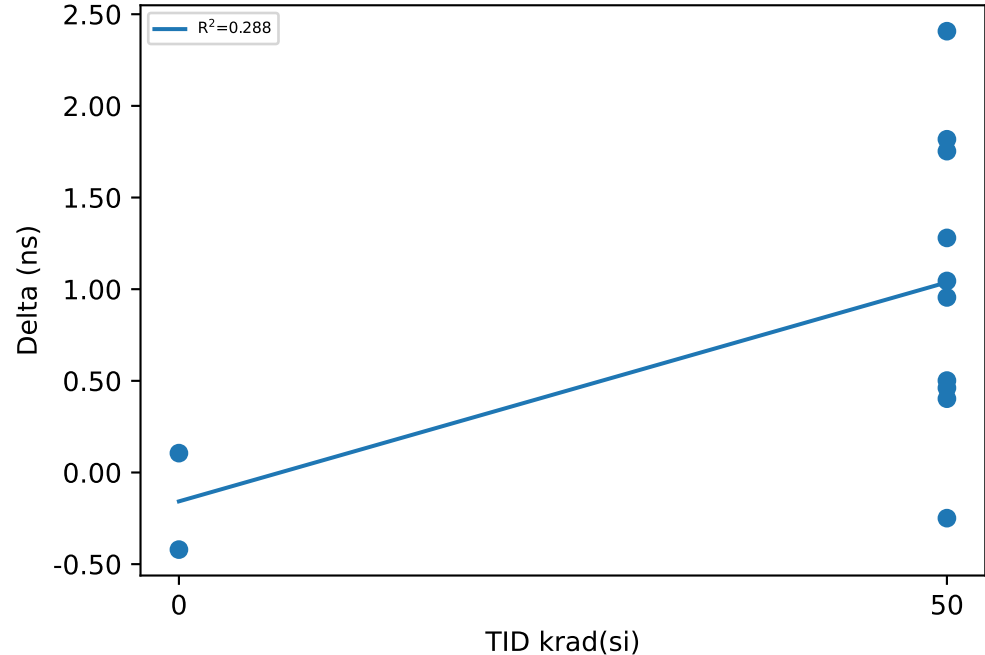
TID vs Result Stats



Test Results (Upper Limit = 115.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	65.078	64.657	-0.4206
2	0	Correlation	65.498	65.604	0.1056
4	50	Bias	65.01	67.417	2.4074
6	50	Bias	65.778	66.733	0.955
7	50	Bias	66.036	67.854	1.8179
8	50	Bias	65.41	67.163	1.753
9	50	Bias	66.286	67.566	1.2797
11	50	Unbias	64.905	65.366	0.4613
12	50	Unbias	64.146	65.191	1.0449
13	50	Unbias	64.483	64.885	0.4026
14	50	Unbias	66.505	66.256	-0.2491
15	50	Unbias	64.349	64.85	0.5015

TID vs Post - Pre Exposure Delta

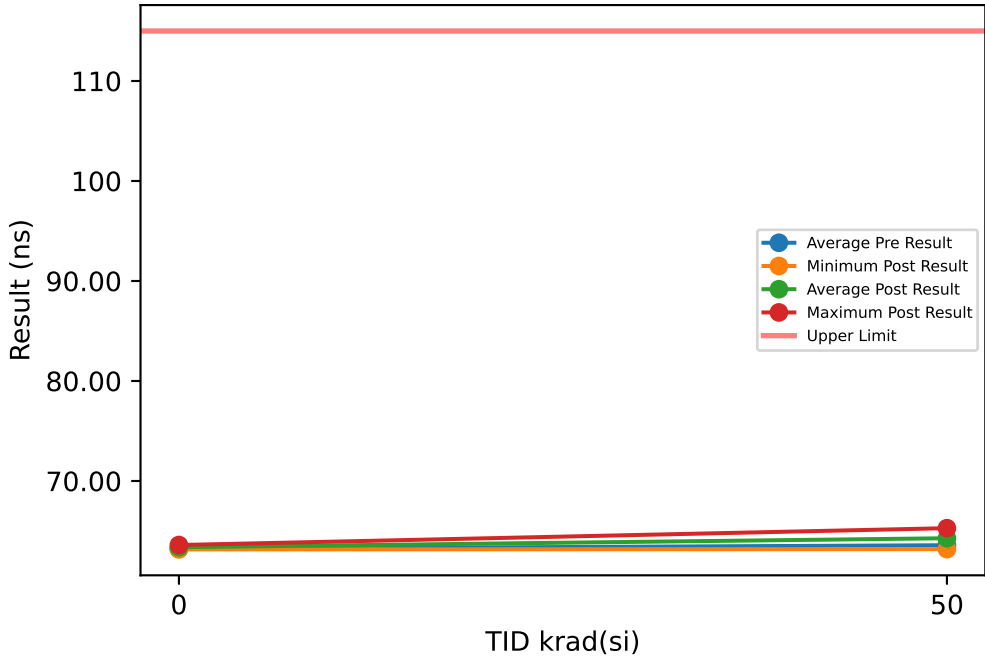


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	65.078	65.288	65.498	0.29713	64.657	65.13	65.604	0.66921	-0.4206	-0.1575	0.1056	0.37208
50	64.146	65.291	66.505	0.84012	64.85	66.328	67.854	1.1737	-0.2491	1.0374	2.4074	0.79867

Device Test: 28.43 CS_ILIM_DELAY(TIMING|DELAY/CS/12/12/0/1000/5/1MHz//@CS_ILIM_DELAY)

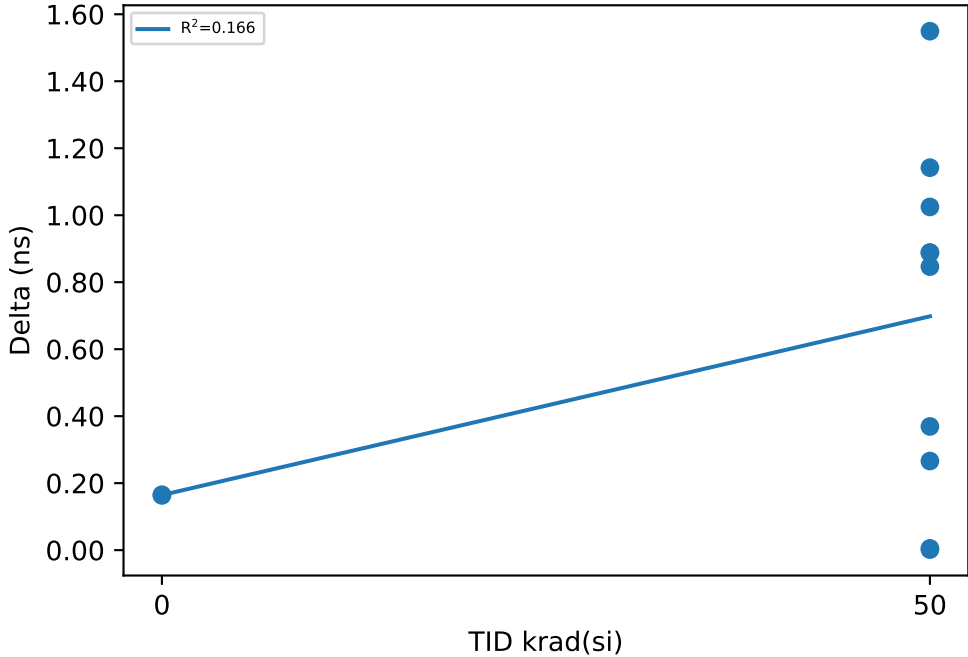
TID vs Result Stats



Test Results (Upper Limit = 115.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	63.434	63.597	0.1634
2	0	Correlation	62.994	63.16	0.1654
4	50	Bias	64.019	64.024	0.0053
6	50	Bias	62.945	63.833	0.8883
7	50	Bias	63.695	65.244	1.5494
8	50	Bias	64.354	65.242	0.8881
9	50	Bias	64.435	65.281	0.8465
11	50	Unbias	62.165	63.189	1.0247
12	50	Unbias	62.298	63.44	1.1419
13	50	Unbias	63.516	63.782	0.266
14	50	Unbias	65.179	65.181	0.0016
15	50	Unbias	63.166	63.535	0.3693

TID vs Post - Pre Exposure Delta

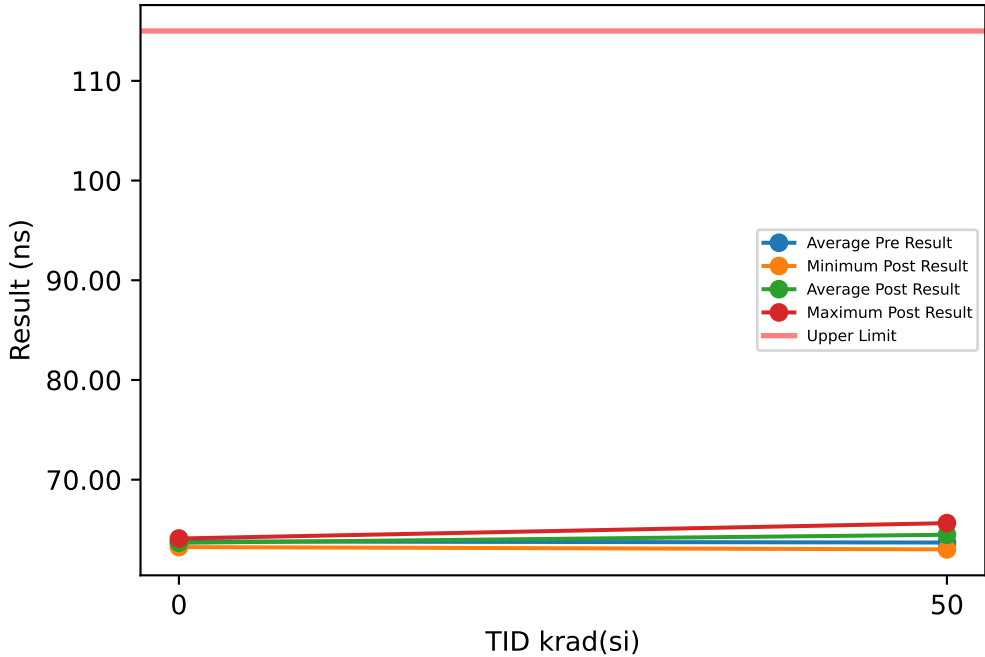


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	62.994	63.214	63.434	0.31091	63.16	63.378	63.597	0.3095	0.1634	0.1644	0.1654	0.0014142
50	62.165	63.577	65.179	0.96145	63.189	64.275	65.281	0.85847	0.0016	0.69811	1.5494	0.51452

Device Test: 28.44 CS_ILIM_DELAY(TIMING|DELAY/CS/14/14/0/1000/5/1MHz//@CS_ILIM_DELAY)

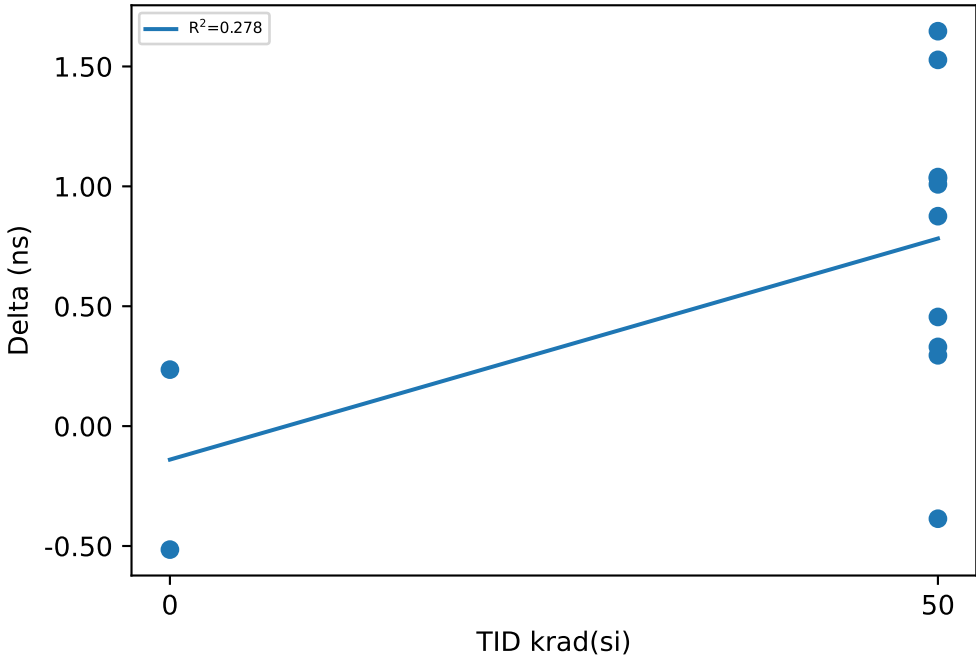
TID vs Result Stats



Test Results (Upper Limit = 115.0 (ns))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	63.754	63.239	-0.515
2	0	Correlation	63.864	64.099	0.2356
4	50	Bias	63.508	64.383	0.8756
6	50	Bias	63.28	64.808	1.5275
7	50	Bias	63.978	65.016	1.0387
8	50	Bias	64.534	64.99	0.4553
9	50	Bias	63.993	65.641	1.6471
11	50	Unbias	62.534	63.542	1.0083
12	50	Unbias	63.393	63.007	-0.3862
13	50	Unbias	63.04	64.073	1.0327
14	50	Unbias	65.224	65.554	0.3304
15	50	Unbias	63.447	63.743	0.2953

TID vs Post - Pre Exposure Delta

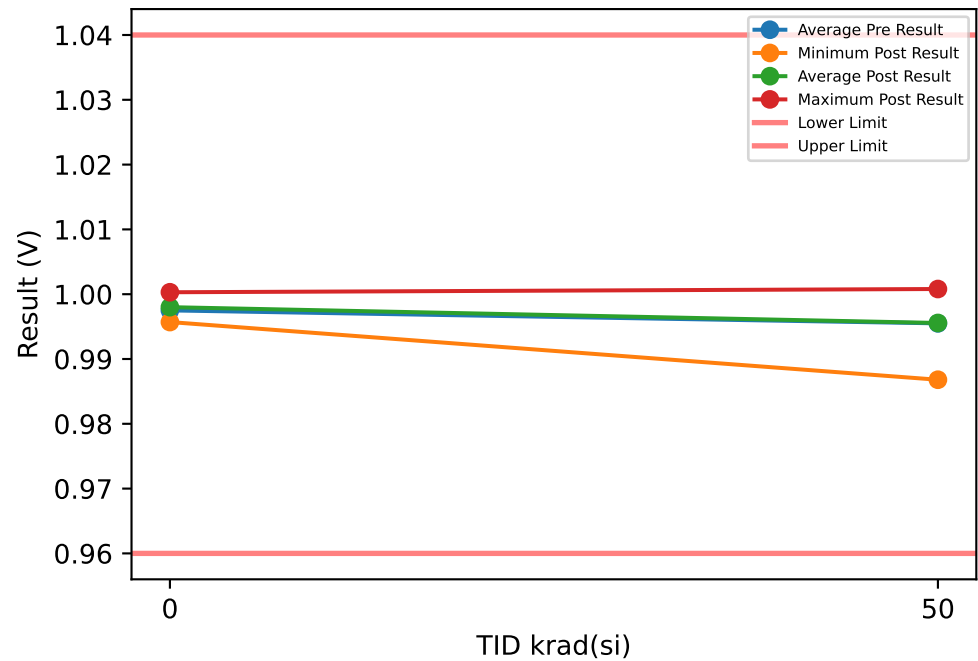


Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	63.754	63.809	63.864	0.077852	63.239	63.669	64.099	0.60861	-0.515	-0.1397	0.2356	0.53075
50	62.534	63.693	65.224	0.77084	63.007	64.476	65.641	0.87712	-0.3862	0.78247	1.6471	0.6151

Device Test: 28.9 V_CS_ILIM_OC(VOLTAGE|OC/CS/4.5/4.5/0/0/4.5/100kHz//@V_CS_ILIM_OC)

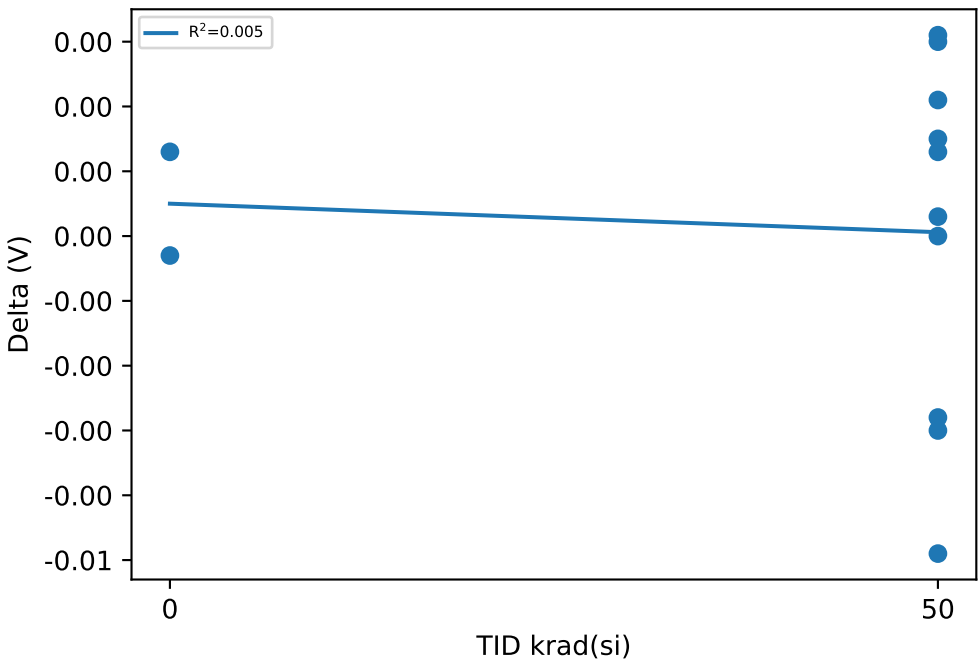
TID vs Result Stats



Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.9944	0.9957	0.0013
2	0	Correlation	1.0006	1.0003	-0.0003
4	50	Bias	0.9917	0.9868	-0.0049
6	50	Bias	0.9917	0.9932	0.0015
7	50	Bias	0.996	0.9991	0.0031
8	50	Bias	0.9958	0.9988	0.003
9	50	Bias	0.9976	0.9989	0.0013
11	50	Unbias	0.9927	0.9897	-0.003
12	50	Unbias	0.993	0.993	0
13	50	Unbias	0.9927	0.9948	0.0021
14	50	Unbias	1.0033	1.0005	-0.0028
15	50	Unbias	1.0005	1.0008	0.0003

TID vs Post - Pre Exposure Delta



Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9944	0.9975	1.0006	0.0043841	0.9957	0.998	1.0003	0.0032527	-0.0003	0.0005	0.0013	0.0011314
50	0.9917	0.9955	1.0033	0.0039637	0.9868	0.99556	1.0008	0.0048284	-0.0049	6e-05	0.0031	0.002746

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